

Service Guide

**Agilent Technologies
8753D
Network Analyzer**



Agilent Technologies

Manufacturing Part Number: 08753-90405

Printed in USA

Print Date: October 1997

Supersedes: September 1997

© Agilent Technologies, Inc. 1997

Hewlett-Packard to Agilent Technologies Transition

This manual may contain references to HP or Hewlett-Packard. Please note that Hewlett-Packard's former test and measurement, semiconductor products and chemical analysis businesses are now part of Agilent Technologies. To reduce potential confusion, the only change to product numbers and names has been in the company name prefix: where a product number/name was HP XXXX the current name/number is now Agilent XXXX. For example, model number HP 8753D is now model number Agilent 8753D.

For the latest information on Agilent's test and measurement products, go to:
www.agilent.com/find/products.

In the U.S., call Agilent Technologies at 1-800-452-4844.

Documentation Warranty

THE MATERIAL CONTAINED IN THIS DOCUMENT IS PROVIDED "AS IS," AND IS SUBJECT TO BEING CHANGED, WITHOUT NOTICE, IN FUTURE EDITIONS. FURTHER, TO THE MAXIMUM EXTENT PERMITTED BY APPLICABLE LAW, AGILENT DISCLAIMS ALL WARRANTIES, EITHER EXPRESS OR IMPLIED WITH REGARD TO THIS MANUAL AND ANY INFORMATION CONTAINED HEREIN, INCLUDING BUT NOT LIMITED TO THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. AGILENT SHALL NOT BE LIABLE FOR ERRORS OR FOR INCIDENTAL OR CONSEQUENTIAL DAMAGES IN CONNECTION WITH THE FURNISHING, USE, OR PERFORMANCE OF THIS DOCUMENT OR ANY INFORMATION CONTAINED HEREIN. SHOULD AGILENT AND THE USER HAVE A SEPARATE WRITTEN AGREEMENT WITH WARRANTY TERMS COVERING THE MATERIAL IN THIS DOCUMENT THAT CONFLICT WITH THESE TERMS, THE WARRANTY TERMS IN THE SEPARATE AGREEMENT WILL CONTROL.

DFARS/Restricted Rights Notice

If software is for use in the performance of a U.S. Government prime contract or subcontract, Software is delivered and licensed as "Commercial computer software" as defined in DFAR 252.227-7014 (June 1995), or as a "commercial item" as defined in FAR 2.101(a) or as "Restricted computer software" as defined in FAR 52.227-19 (June 1987) or any equivalent agency regulation or contract clause. Use, duplication or disclosure of Software is subject to Agilent Technologies' standard commercial license terms, and non-DOD Departments and Agencies of the U.S. Government will receive no greater than Restricted Rights as defined in FAR 52.227-19(c)(1-2) (June 1987). U.S. Government users will receive no greater than Limited Rights as defined in FAR 52.227-14 (June 1987) or DFAR 252.227-7015 (b)(2) (November 1995), as applicable in any technical data.

Printing Copies of Documentation from the Web

To print copies of documentation from the Web, download the PDF file from the Agilent web site:

- Go to <http://www.agilent.com>.
- Enter the document's part number (located on the title page) in the **Quick Search** box.
- Click GO.
- Click on the hyperlink for the document.
- Click the printer icon located in the tool bar.

Contacting Agilent

This information supersedes all prior HP contact information.

Online assistance: www.agilent.com/find/assist

Americas

Brazil (tel) (+55) 11 3351 7012 (fax) (+55) 11 3351 7024	Canada (tel) +1 877 894 4414 (fax) +1 303 662 3369	Mexico (tel) 1 800 254 2440 (fax) 1 800 254 4222	United States (tel) 800 829 4444 (alt) (+1) 303 662 3998 (fax) 800 829 4433
---	---	---	---

Asia Pacific and Japan

Australia (tel) 1 800 225 574 (fax) 1 800 681 776 (fax) 1 800 225 539	China (tel) 800 810 0508 (alt) 800 810 0510 (fax) 800 810 0507 (fax) 800 810 0362	Hong Kong (tel) 800 933 229 (fax) 800 900 701	India (tel) 1600 112 626 (fax) 1600 112 727 (fax) 1600 113 040
Japan (Bench) (tel) 0120 32 0119 (alt) (+81) 426 56 7799 (fax) 0120 01 2144	Japan (On-Site) (tel) 0120 802 363 (alt) (+81) 426 56 7498 (fax) (+81) 426 60 8953	Singapore (tel) 1 800 275 0880 (fax) (+65) 6755 1235 (fax) (+65) 6755 1214	South Korea (tel) 080 778 0011 (fax) 080 778 0013
Taiwan (tel) 0800 047 669 (fax) 0800 047 667 (fax) 886 3492 0779	Thailand (tel) 1 800 2758 5822 (alt) (+66) 2267 5913 (fax) 1 800 656 336	Malaysia (tel) 1800 880 399 (fax) 1800 801 054	

Europe

Austria (tel) 0820 87 44 11* (fax) 0820 87 44 22	Belgium (tel) (+32) (0)2 404 9340 (alt) (+32) (0)2 404 9000 (fax) (+32) (0)2 404 9395	Denmark (tel) (+45) 7013 1515 (alt) (+45) 7013 7313 (fax) (+45) 7013 1555	Finland (tel) (+358) 10 855 2100 (fax) (+358) (0) 10 855 2923
France (tel) 0825 010 700* (alt) (+33) (0)1 6453 5623 (fax) 0825 010 701*	Germany (tel) 01805 24 6333* (alt) 01805 24 6330* (fax) 01805 24 6336*	Ireland (tel) (+353) (0)1 890 924 204 (alt) (+353) (0)1 890 924 206 (fax) (+353) (0)1 890 924 024	Israel (tel) (+972) 3 9288 500 (fax) (+972) 3 9288 501
Italy (tel) (+39) (0)2 9260 8484 (fax) (+39) (0)2 9544 1175	Luxemburg (tel) (+32) (0)2 404 9340 (alt) (+32) (0)2 404 9000 (fax) (+32) (0)2 404 9395	Netherlands (tel) (+31) (0)20 547 2111 (alt) (+31) (0)20 547 2000 (fax) (+31) (0)20 547 2190	Russia (tel) (+7) 095 797 3963 (alt) (+7) 095 797 3900 (fax) (+7) 095 797 3901
Spain (tel) (+34) 91 631 3300 (alt) (+34) 91 631 3000 (fax) (+34) 91 631 3301	Sweden (tel) 0200 88 22 55* (alt) (+46) (0)8 5064 8686 (fax) 020 120 2266*	Switzerland (French) (tel) 0800 80 5353 opt. 2* (alt) (+33) (0)1 6453 5623 (fax) (+41) (0)22 567 5313	Switzerland (German) (tel) 0800 80 5353 opt. 1* (alt) (+49) (0)7031 464 6333 (fax) (+41) (0)1 272 7373
Switzerland (Italian) (tel) 0800 80 5353 opt. 3* (alt) (+39) (0)2 9260 8484 (fax) (+41) (0)22 567 5314	United Kingdom (tel) (+44) (0)7004 666666 (alt) (+44) (0)7004 123123 (fax) (+44) (0)7004 444555		

(tel) = primary telephone number; (alt) = alternate telephone number; (fax) = FAX number; * = in country number

11/16/04

Service Guide
HP 8753D Network Analyzer



Printed in USA

HP part number: 08753-90405 Supersedes September 1997
Printed in USA October 1997

Notice.

The information contained in this document is subject to change without notice.

Hewlett-Packard makes no warranty of any kind with regard to this material, including but not limited to, the implied warranties of merchantability and fitness for a particular purpose. Hewlett-Packard shall not be liable for errors contained herein or for incidental or consequential damages in connection with the furnishing, performance, or use of this material.

©Copyright Hewlett-Packard Company 1995, 1996, 1997
All Rights Reserved. Reproduction, adaptation, or translation without prior
written permission is prohibited, except as allowed under the copyright laws.
1400 Fountaingrove Parkway, Santa Rosa, CA 95403-1799, USA

HP 8753D Network Analyzer Documentation Set



The **Installation and Quick Start Guide** familiarizes you with the HP 8753D network analyzer's front and rear panels, electrical and environmental operating requirements, as well as procedures for installing, configuring, and verifying the operation of the HP 8753D.



The **User's Guide** shows how to make measurements, explains commonly-used features, and tells you how to get the most performance from your analyzer.



The **Quick Reference Guide** provides a summary of selected user features.



The **Programmer's Guide** provides programming information including: an HP-IB command reference, an HP-IB programming reference, as well as programming examples.



The **System Verification and Test Guide** provides the system verification and performance tests and the Performance Test Record for your HP 8753D network analyzer.

Contents

1. Service Equipment and Analyzer Options

Table of Service Test Equipment	1-1
Principles of Microwave Connector Care	1-4
Analyzer Options Available	1-6
Option 1D5, High Stability Frequency Reference	1-6
Option 002, Harmonic Mode	1-6
Option 006, 6 GHz Operation	1-6
Option 010, Time Domain	1-6
Option 011, Receiver Configuration	1-6
Option 075, 75Ω Impedance	1-7
Option 1CM, Rack Mount Flange Kit Without Handles	1-7
Option 1CP, Rack Mount Flange Kit With Handles	1-7
Service and Support Options	1-8
Option W31	1-8
Option W51	1-8
Option W32	1-8
Option W52	1-8
Option W34	1-8
Option W54	1-9

2. System Verification and Performance Tests

How to Test the Performance of Your Analyzer	2-2
Sections in this Chapter	2-2
Performance Test Record	2-4
System Verification Cycle and Kit Re-certification	2-5
How to Select the System Verification Procedure	2-5
HP 8753D Automated Mode System Verification	2-6
Initialization	2-6
Measurement Calibration	2-8
Device Verification	2-10
In Case of Difficulty	2-13
HP 8753D Manual Mode System Verification	2-14

Initialization	2-14
Measurement Calibration	2-15
Device Verification	2-17
In Case of Difficulty	2-22
1. Test Port Output Frequency Range and Accuracy	2-23
In Case of Difficulty	2-25
2. External Source Mode Frequency Range	2-26
In Case of Difficulty	2-27
3. Test Port Output Power Accuracy	2-28
In Case of Difficulty	2-30
4. Test Port Output Power Range and Linearity	2-31
In Case of Difficulty	2-33
5. Minimum R Channel Level	2-34
In Case of Difficulty	2-36
6. Test Port Input Noise Floor Level	2-40
Port 1 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 3 kHz)	2-41
Port 1 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 10 Hz)	2-42
Port 2 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 10 Hz)	2-42
Port 2 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 3 kHz)	2-43
Port 2 Noise Floor Level from 3 GHz to 6 GHz (IF BW = 3 kHz)	2-43
Port 2 Noise Floor Level from 3 GHz to 6 GHz (IF BW = 10 Hz)	2-44
Port 1 Noise Floor Level for 3 GHz to 6 GHz (IF BW = 10 Hz) . .	2-44
Port 1 Noise Floor Level from 3 GHz to 6 GHz (IF BW = 3 kHz)	2-44
In Case of Difficulty	2-45
7. Test Port Input Frequency Response	2-46
Power Meter Calibration for Test Port 1 from 300 kHz to 3 GHz .	2-47
Test Port 2 Input Frequency Response from 300 kHz to 3GHz . .	2-50
Power Meter Calibration on Port 2 from 300 kHz to 3 GHz . . .	2-51
Test Port 1 Input Frequency Response from 300 kHz to 3 GHz . .	2-52
Power Meter Calibration for Test Port 2 from 3 GHz to 6 GHz . .	2-52
Test Port 1 Input Frequency Response from 3 GHz to 6 GHz . . .	2-54
Power Meter Calibration on Test Port 1 from 3 GHz to 6 GHz . .	2-55
Test Port 2 Input Frequency Response from 3 GHz to 6 GHz . . .	2-56
In Case of Difficulty	2-56
8. Test Port Crosstalk	2-57
Crosstalk to Test Port 2 from 300 kHz to 3 GHz	2-59
Crosstalk to Test Port 1 from 300 kHz to 3 GHz	2-59
Crosstalk to Test Port 1 from 3 GHz to 6 GHz	2-59
Crosstalk to Test Port 2 from 3 GHz to 6 GHz	2-60
In Case of Difficulty	2-60
9. Calibration Coefficients	2-62

Contents-2

First Full 2-Port Calibration	2-63
Directivity (Forward) Calibration Coefficient	2-65
Source Match (Forward) Calibration Coefficient	2-65
Transmission Tracking (Forward) Calibration Coefficient	2-65
Reflection Tracking (Forward) Calibration Coefficient	2-65
Load Match (Reverse) Calibration Coefficient	2-65
Transmission Tracking (Reverse) Calibration Coefficient	2-66
Second Full 2-Port Calibration	2-66
Load Match (Forward) Calibration Coefficient	2-68
Directivity (Reverse) Calibration Coefficient	2-68
Source Match (Reverse) Calibration Coefficient	2-68
Reflection Tracking (Reverse) Calibration Coefficient	2-68
10. System Trace Noise (Only for Analyzers without Option 006)	2-69
System Trace Noise for A/R Magnitude	2-70
System Trace Noise for A/R Phase	2-70
System Trace Noise for B/R Magnitude	2-70
System Trace Noise for B/R Phase	2-71
In Case of Difficulty	2-71
11. System Trace Noise (Only for Analyzers with Option 006)	2-72
System Trace Noise for A/R Magnitude from 30 kHz to 3 GHz	2-73
System Trace Noise for A/R Magnitude from 3 GHz to 6 GHz	2-73
System Trace Noise for A/R Phase from 3 GHz to 6 GHz	2-73
System Trace Noise for A/R Phase from 30 kHz to 3 GHz	2-74
System Trace Noise for B/R Magnitude from 30 kHz to 3 GHz	2-74
System Trace Noise for B/R Magnitude from 3 GHz to 6 GHz	2-74
System Trace Noise for B/R Phase from 3 GHz to 6 GHz	2-74
System Trace Noise for B/R Phase from 30 kHz to 3 GHz	2-75
In Case of Difficulty	2-75
12. Test Port Input Impedance	2-76
In Case of Difficulty	2-80
13. Test Port Receiver Magnitude Dynamic Accuracy	2-81
Test Port 2 Magnitude Dynamic Accuracy	2-83
Initial Calculations	2-83
Setup and Measurements	2-84
Test Port 1 Magnitude Dynamic Accuracy	2-87
In Case of Difficulty	2-90
14. Test Port Receiver Phase Dynamic Accuracy	2-91
Test Port 2 Phase Dynamic Accuracy	2-91
Test Port 1 Phase Dynamic Accuracy	2-92
15. Test Port Receiver Magnitude Compression	2-93
Test Port 2 Magnitude Compression	2-93

Test Port 1 Magnitude Compression	2-95
In Case of Difficulty	2-95
16. Test Port Receiver Phase Compression	2-96
Test Port 2 Phase Compression	2-96
Test Port 1 Phase Compression	2-98
In Case of Difficulty	2-98
17. Test Port Output/Input Harmonics (Option 002 Analyzers without Option 006 Only)	2-99
Test Port Output Worst Case 2nd Harmonic	2-100
Test Port Output Worst Case 3rd Harmonic	2-101
Port 1 Input Worst Case 2nd Harmonic	2-101
Port 1 Input Worst Case 3rd Harmonic	2-102
Port 2 Input Worst Case 2nd Harmonic	2-103
Port 2 Input Worst Case 3rd Harmonic	2-103
18. Test Port Output/Input Harmonics (Option 002 Analyzers with Option 006 Only)	2-104
Test Port Output Worst Case 2nd Harmonic	2-105
Test Port Output Worst Case 3rd Harmonic	2-106
Port 1 Input Worst Case 2nd Harmonic	2-107
Port 1 Input Worst Case 3rd Harmonic	2-108
Port 2 Input Worst Case 2nd Harmonic	2-108
Port 2 Input Worst Case 3rd Harmonic	2-109
2a. Performance Test Record	
For Analyzers with a Frequency Range of 30 kHz to 3 GHz	2a-1
2b. Performance Test Record	
For Analyzers with a Frequency Range of 30 kHz to 6 GHz	2b-1
3. Adjustments and Correction Constants	
Post-Repair Procedures for HP 8753D	3-2
A9 CC Jumper Positions	3-6
Source Default Correction Constants (Test 44)	3-7
Source Pretune Default Correction Constants (Test 45)	3-8
Analog Bus Correction Constants (Test 46)	3-9
RF Output Power Correction Constants (Test 47)	3-10
Power Sensor Calibration Factor Entry	3-11
Source Pretune Correction Constants (Test 48)	3-14
Display Intensity Adjustments (Test 49)	3-15
Background Adjustment	3-16
Maximum Intensity Adjustment	3-16

Contents-4

Operating Default Intensity Adjustment	3-18
IF Amplifier Correction Constants (Test 51)	3-19
ADC Offset Correction Constants (Test 52)	3-20
Sampler Magnitude and Phase Correction Constants (Test 53)	3-21
Power Sensor Calibration Factor Entry	3-22
Determine the Insertion Loss of the Cable at 1 GHz	3-23
Sampler Correction Constants Routine	3-25
Cavity Oscillator Frequency Correction Constants (Test 54)	3-31
Spur Search Procedure with a Filter	3-33
Spurs Search Procedure without a Filter	3-34
Serial Number Correction Constants (Test 55)	3-37
Option Numbers Correction Constants (Test 56)	3-39
Calibration Kit Default Correction Constants (Test 57)	3-40
Initialize EEPROMs (Test 58)	3-41
EEPROM Backup Disk Procedure	3-42
How to Retrieve Correction Constant Data from the EEPROM	
Backup Disk	3-43
Vertical Position and Focus Adjustments	3-44
Vertical Adjustment Procedure	3-45
Focus Adjustment Procedure	3-45
Display Degaussing (Demagnetizing)	3-46
Fractional-N Frequency Range Adjustment	3-47
Frequency Accuracy Adjustment	3-50
HP 8753D with Option 1D5 Only	3-52
High/Low Band Transition Adjustment	3-54
Fractional-N Spur Avoidance and FM Sideband Adjustment	3-56
Source Spur Avoidance Tracking Adjustment	3-60
Unprotected Hardware Option Numbers Correction Constants	3-62
Sequences for Mechanical Adjustments	3-64
How to Load Sequences from Disk	3-64
How to Set Up the Fractional-N Frequency Range Adjustment	3-65
How to Set Up the High/Low Band Transition Adjustments	3-65
How to Set Up the Fractional-N Spur Avoidance and FM Sideband Adjustment	3-66
Sequence Contents	3-66
Sequence for the High/Low Band Transition Adjustment	3-66
Sequences for the Fractional-N Frequency Range Adjustment	3-67
Sequences for the Fractional-N Avoidance and FM Sideband Adjustment	3-68

4. Start Troubleshooting Here	
Assembly Replacement Sequence	4-2
Having Your Analyzer Serviced	4-2
Step 1. Initial Observations	4-3
Initiate the Analyzer Self-Test	4-3
If the Self-Test Failed	4-3
Step 2. Operator's Check	4-4
Equipment	4-4
Procedure	4-4
If the Operator's Check Failed	4-4
Step 3. HP-IB Systems Check	4-5
If Using a Plotter or Printer	4-6
If Using an External Disk Drive	4-6
Troubleshooting Systems with Multiple Peripherals	4-7
Troubleshooting Systems with Controllers	4-7
Step 4. Faulty Group Isolation	4-8
Power Supply	4-9
Check the Rear Panel LEDs	4-9
Check the A8 Post Regulator LEDs	4-9
Digital Control	4-10
Observe the Power Up Sequence	4-10
Verify Internal Tests Passed	4-11
Source	4-12
Phase Lock Error Messages	4-12
Check Source Output Power	4-12
No Oscilloscope or Power Meter? Try the ABUS	4-14
Receiver	4-15
Observe the A and B Input Traces	4-15
Receiver Error Messages	4-16
Faulty Data	4-17
Accessories	4-18
Accessories Error Messages	4-18
5. Power Supply Troubleshooting	
Assembly Replacement Sequence	5-2
Simplified Block Diagram	5-3
Start Here	5-4
Check the Green LED and Red LED on A15	5-4
Check the Green LEDs on A8	5-5
Measure the Post Regulator Voltages	5-5
If the Green LED of the A15 Is not ON Steadily	5-7

Check the Line Voltage, Selector Switch, and Fuse	5-7
If the Red LED of the A15 is ON	5-8
Check the A8 Post Regulator	5-8
Verify the A15 Preregulator	5-9
Check for a Faulty Assembly	5-11
Check the Operating Temperature	5-13
Inspect the Motherboard	5-13
If the Green LEDs of the A8 are not All ON	5-14
Remove A8, Maintain A15W1 Cable Connection	5-14
Check the A8 Fuses and Voltages	5-14
Remove the Assemblies	5-15
Briefly Disable the Shutdown Circuitry	5-16
Inspect the Motherboard	5-18
Error Messages	5-19
Check the Fuses and Isolate A8	5-20
Fan Troubleshooting	5-21
Fan Speeds	5-21
Check the Fan Voltages	5-21
Short A8TP3 to Ground	5-21
Intermittent Problems	5-22
6. Digital Control Troubleshooting	
Assembly Replacement Sequence	6-2
Digital Control Group Block Diagram	6-3
Check A9 CPU Operation	6-4
A9 CC Jumper Positions	6-4
Checking A9 CPU Red LED Patterns	6-5
Check A19 GSP and A18 Display Operation	6-7
Cycle Power and Look at the Display	6-7
Perform Display Intensity and Focus Adjustments	6-7
A1/A2 Front Panel Troubleshooting	6-7
Check Front Panel LEDs After Preset	6-7
Identify the Stuck Key	6-8
Inspect Cables	6-10
Test Using a Controller	6-11
Run the Internal Diagnostic Tests	6-11
A19 GSP and A18 Display Troubleshooting	6-13
Measure Display Power Supply Voltages on A19	6-13
Measure Display Power Supply Voltages Entering A19	6-13
Run Display Test 59	6-14
Inspect Ribbon Cable Repeat Display Test 59	6-15

Perform Walking One Pattern	6-15
Run Display Tests 60-65	6-17
If the Fault is Intermittent	6-18
Repeat Test Function	6-18
HP-IB Failures	6-18
7. Source Troubleshooting	
Assembly Replacement Sequence	7-2
Before You Start Troubleshooting	7-2
Power	7-3
1. Source Default Correction Constants (Test 44)	7-3
2. RF Output Power Correction Constants (Test 47)	7-3
3. Sampler Magnitude and Phase Correction Constants (Test 53)	7-3
Phase Lock Error	7-4
Phase Lock Loop Error Message Check	7-4
A4 Sampler/Mixer Check	7-6
A3 Source and A11 Phase Lock Check	7-7
YO Coil Drive Check with Analog Bus	7-10
YO Coil Drive Check with Oscilloscope	7-11
A12 Reference Check	7-12
Analog Bus Method	7-12
Oscilloscope Method	7-14
100 kHz Pulses	7-15
PLREF Waveforms	7-16
REF Signal At A11TP1 Pin 9	7-16
High Band REF Signal	7-16
Low Band REF Signal	7-17
FN LO at A12 Check	7-18
4 MHz Reference Signal	7-19
2ND LO Waveforms	7-20
90 Degree Phase Offset of 2nd LO Signals in High Band	7-20
In-Phase 2nd LO Signals in Low Band	7-20
A12 Digital Control Signals Check	7-22
L ENREF Line	7-22
L HB and L LB Lines	7-23
A13/A14 Fractional-N Check	7-23
Fractional-N Check with Analog Bus	7-23
A14 VCO Range Check with Oscilloscope	7-24
A14 VCO Exercise	7-26
A14 Divide-by-N Circuit Check	7-28
A14-to-A13 Digital Control Signals Check	7-28

H MB Line	7-30
A7 Pulse Generator Check	7-31
A7 Pulse Generator Check with Spectrum Analyzer	7-31
Rechecking the A13/A14 Fractional-N	7-32
A7 Pulse Generator Check with Oscilloscope	7-33
A11 Phase Lock Check	7-34
Phase Lock Check with PLL DIAG	7-35
Phase Lock Check by Signal Examination	7-35
Source Group Troubleshooting Appendix	7-37
Troubleshooting Source Problems with the Analog Bus	7-37
Phase Lock Diagnostic Tools	7-37
Phase Lock Error Messages	7-37
Phase Lock Diagnostic Routines	7-38
Broadband Power Problems	7-38
8. Receiver Troubleshooting	
Assembly Replacement Sequence	8-2
Receiver Failure Error Messages	8-3
Check the A and B Inputs	8-4
Troubleshooting When All Inputs Look Bad	8-6
Run Internal Tests 18 and 17	8-6
Check 2nd LO	8-6
Check the 4 MHz REF Signal	8-7
Check A10 by Substitution or Signal Examination	8-8
Troubleshooting When One or More Inputs Look Good	8-11
Check the 4 kHz Signal	8-11
Check the Trace with the Sampler Correction Constants Off	8-12
Check 1st LO Signal at Sampler/Mixer	8-14
Check 2nd LO Signal at Sampler/Mixer	8-14
9. Accessories Troubleshooting	
Assembly Replacement Sequence	9-2
Inspect the Accessories	9-3
Inspect the Test Port Connectors and Calibration Devices	9-3
Inspect the Error Terms	9-3
Cable Test	9-5
Verify Shorts and Opens	9-6

10. Service Key Menus and Error Messages

Service Key Menus	10-1
Error Messages	10-1
Service Key Menus - Internal Diagnostics	10-2
Tests Menu	10-3
Test Options Menu	10-5
Self Diagnose Softkey	10-7
Test Descriptions	10-7
Internal Tests	10-7
External Tests	10-11
System Verification Tests	10-12
Adjustment Tests	10-13
Display Tests	10-15
Test Patterns	10-16
Service Key Menus - Service Features	10-18
Service Modes Menu	10-18
Service Modes More Menu	10-21
Analog Bus	10-22
Description of the Analog Bus	10-22
The Main ADC	10-23
The Frequency Counter	10-23
Analog In Menu	10-24
Analog Bus Nodes	10-26
A3 Source	10-26
A10 Digital IF	10-33
A11 Phase Lock	10-34
A12 Reference	10-40
A14 Fractional-N (Digital)	10-43
PEEK/POKE Menu	10-46
Firmware Revision Softkey	10-47
HP-IB Service Mnemonic Definitions	10-48
Invoking Tests Remotely	10-48
Analog Bus Codes	10-49
Error Messages	10-50

11. Error Terms	
Error Terms Can Also Serve a Diagnostic Purpose	11-1
Full Two-Port Error-Correction Procedure	11-3
Error Term Inspection	11-7
If Error Terms Seem Worse than Typical Values	11-8
Uncorrected Performance	11-8
Error Term Descriptions	11-9
Directivity (EDF and EDR)	11-10
Description	11-10
Significant System Components	11-10
Affected Measurements	11-10
Source Match (ESF and ESR)	11-11
Description	11-11
Significant System Components	11-11
Affected Measurements	11-11
Reflection Tracking (ERF and ERR)	11-12
Description	11-12
Significant System Components	11-12
Affected Measurements	11-12
Isolation (Crosstalk, EXF and EXR)	11-13
Description	11-13
Significant System Components	11-13
Affected Measurements	11-13
Load Match (ELF and ELR)	11-14
Description	11-14
Significant System Components	11-14
Affected Measurements	11-14
Transmission Tracking (ETF and ETR)	11-15
Description	11-15
Significant System Components	11-15
Affected Measurements	11-15

12. Theory of Operation	
How the HP 8753D Works	12-1
The Built-In Synthesized Source	12-2
The Source Step Attenuator	12-2
The Built-In Test Set	12-3
The Receiver Block	12-3
The Microprocessor	12-3
Required Peripheral Equipment	12-3
A Close Look at the Analyzer's Functional Groups	12-4

Power Supply Theory	12-5
A15 Preregulator	12-5
Line Power Module	12-6
Preregulated Voltages	12-6
Regulated +5 V Digital Supply	12-6
Shutdown Indications: the Green LED and Red LED	12-6
A8 Post Regulator	12-7
Voltage Indications: the Green LEDs	12-7
Shutdown Circuit	12-7
Variable Fan Circuit and Air Flow Detector	12-7
Display Power	12-8
Probe Power	12-8
Digital Control Theory	12-8
A1 Front Panel	12-10
A2 Front Panel Processor	12-10
A9 CPU/A10 Digital IF	12-10
Main CPU	12-10
Main RAM	12-11
EEPROM	12-11
Digital Signal Processor	12-11
A18 Display	12-11
A19 GSP	12-11
A16 Rear Panel	12-12
Source Theory Overview	12-13
A14/A13 Fractional-N	12-13
A12 Reference	12-13
A7 Pulse Generator	12-14
A11 Phase Lock	12-14
A3 Source	12-14
Source Super Low Band Operation	12-14
Source Low Band Operation	12-15
Source High Band Operation	12-18
Source Operation in other Modes/Features	12-21
Frequency Offset	12-21
Harmonic Analysis (Option 002)	12-21
External Source Mode	12-22
Tuned Receiver Mode	12-24
Signal Separation	12-25
The Built-In Test Set	12-25
A21 and A22 Test Port Couplers	12-25
A23 LED Front Panel	12-25

Contents-12

A24 Transfer Switch	12-25
A25 Test Set Interface	12-25
Receiver Theory	12-27
A4/A5/A6 Sampler/Mixer	12-28
The Sampler Circuit in High Band	12-28
The Sampler Circuit in Low Band or Super Low Band	12-28
The 2nd LO Signal	12-28
The Mixer Circuit	12-29
A10 Digital IF	12-29
13. Replaceable Parts	
Replacing an assembly	13-2
Rebuilt-Exchange Assemblies	13-3
Ordering Information	13-3
Replaceable Part Listings	13-5
Major Assemblies, Top	13-6
Major Assemblies, Bottom	13-8
Cables, Top	13-10
Cables, Bottom	13-12
Cables, Front	13-14
Cables, Rear	13-16
Cables, Source	13-18
Front Panel Assembly, Outside	13-20
Front Panel Assembly, Inside	13-22
Rear Panel Assembly	13-24
Rear Panel Assembly, Option 1D5	13-26
Hardware, Top	13-28
Hardware, Bottom	13-30
Hardware, Front	13-32
Hardware, Test Set Deck	13-34
Hardware, Disk Drive Support	13-36
Hardware, Memory Deck	13-37
Hardware, Fan	13-38
Hardware, Preregulator	13-39
Chassis Parts, Outside	13-40
Chassis Parts, Inside	13-42
Miscellaneous	13-44

14. Assembly Replacement and Post-Repair Procedures	
Replacing an assembly	14-2
Procedures described in this chapter	14-3
Line Fuse	14-4
Tools Required	14-4
Removal	14-4
Replacement	14-4
Covers	14-6
Tools Required	14-6
Removing the top cover	14-6
Removing the side covers	14-6
Removing the bottom cover	14-6
Front Panel Assembly	14-8
Tools Required	14-8
Removal	14-8
Replacement	14-10
Rear Panel Assembly	14-12
Tools Required	14-12
Removal	14-12
Replacement	14-14
Test Set Deck	14-16
Tools Required	14-16
Removal	14-16
Replacement	14-18
A1 Keyboard	14-20
Tools Required	14-20
Removal	14-20
Replacement	14-20
A2 Front Panel Interface	14-22
Tools Required	14-22
Removal	14-22
Replacement	14-22
A3 Source Assembly	14-24
Tools Required	14-24
Removal	14-24
Replacement	14-24
A4, A5, A6 Samplers and A7 Pulse Generator	14-26
Tools Required	14-26
Removal	14-26
Replacement	14-26
A8, A10, A11, A12, A13, A14 Card Cage Boards	14-28

Tools Required	14-28
Removal	14-28
Replacement	14-28
A9 CPU Board	14-30
Tools Required	14-30
Removal	14-30
Replacement	14-30
A9BT1 Battery	14-32
Tools Required	14-32
Removal	14-32
Replacement	14-32
A15 Preregulator	14-34
Tools Required	14-34
Removal	14-34
Replacement	14-34
A16 Rear Panel Interface	14-36
Tools Required	14-36
Removal	14-36
Replacement	14-36
A17 Motherboard Assembly	14-38
Tools Required	14-38
Removal	14-38
Replacement	14-40
A18 Display	14-42
Tools Required	14-42
Removal	14-42
Replacement	14-42
A19 Graphics Processor	14-44
Tools Required	14-44
Removal	14-44
Replacement	14-44
A20 Disk Drive	14-46
Tools Required	14-46
Removal	14-46
Replacement	14-46
A21, A22 Test Port Couplers	14-48
Tools Required	14-48
Removal	14-48
Replacement	14-48
A23 LED Board	14-50
Tools Required	14-50

Removal	14-50
Replacement	14-50
A24 Transfer Switch	14-52
Tools Required	14-52
Removal	14-52
Replacement	14-52
A25 Test Set Interface	14-54
Tools Required	14-54
Removal	14-54
Replacement	14-54
A26 High Stability Frequency Reference (Option 1D5)	14-56
Tools Required	14-56
Removal	14-56
Replacement	14-56
B1 Fan	14-58
Tools Required	14-58
Removal	14-58
Replacement	14-58
Post-Repair Procedures for HP 8753D	14-60

15. Safety and Licensing

Notice	15-1
Certification	15-1
Warranty	15-2
Assistance	15-2
Shipment for Service	15-4
Safety Symbols	15-5
Instrument Markings	15-5
General Safety Considerations	15-6
Safety Earth Ground	15-6
Before Applying Power	15-6
Servicing	15-6

Index

Figures

2-1. System Verification Test Setup	2-6
2-2. Connections for Measurement Calibration Standards	2-8
2-3. Transmission Calibration Setup	2-9
2-4. Connections for the 20 dB Verification Device	2-10
2-5. Connections for the 50 dB Verification Device	2-11
2-6. Mismatch Device Verification Setup	2-11
2-7. Mismatch Device Verification Setup	2-12
2-8. System Verification Test Setup	2-14
2-9. Transmission Calibration Setup	2-17
2-10. Connections for the 20 dB Verification Device	2-18
2-11. Connections for the 50 dB Verification Device	2-19
2-12. Mismatch Device Verification Setup	2-20
2-13. Mismatch Device Verification Setup	2-21
2-14. Test Port Output Frequency Range and Accuracy Test Setup	2-24
2-15. External Source Mode Frequency Range Test Setup	2-26
2-16. Source Output Power Accuracy Test Setup	2-29
2-17. Test Port Output Power Range and Accuracy Test Setup	2-32
2-18. Minimum R Channel Level Test Setup	2-34
2-19. Flexible RF Cable Location	2-37
2-20. Connections for Substituting the R Sampler (A4)	2-38
2-21. Setup for Checking the R Sampler (A4)	2-39
2-22. Source Input Noise Floor Test Setup	2-41
2-23. Setup for Power Meter Calibration on Test Port 1	2-47
2-24. Test Port 2 Input Frequency Response Test Setup	2-50
2-25. Setup for Power Meter Calibration on Test Port 2	2-51
2-26. Test Port 1 Input Frequency Response Test Setup	2-52
2-27. Setup for Power Meter Calibration on Test Port 2	2-53
2-28. Setup for Test Port 1 Input Frequency Response	2-54
2-29. Setup for Power Meter Calibration on Test Port 1	2-55
2-30. Test Port 2 Input Frequency Response Test Setup	2-56
2-31. Test Port Crosstalk Test Setup	2-58
2-32. HP 8753D Bottom View	2-61

2-33. First Full 2-Port Calibration Test Setup	2-63
2-34. Transmission Calibration Test Setup	2-64
2-35. Second Full 2-Port Calibration Test Setup	2-66
2-36. Transmission Calibration Test Setup	2-67
2-37. System Trace Noise Test Setup	2-69
2-38. System Trace Noise Test Setup	2-72
2-39. S11 1-Port Cal Test Setup	2-77
2-40. Test Port 2 Input Impedance Test Setup	2-78
2-41. S22 1-Port Cal Test Setup	2-79
2-42. Test Port 1 Input Impedance Test Setup	2-80
2-43. Receiver Magnitude Dynamic Accuracy	2-81
2-44. Test Port 2 Dynamic Accuracy Test Setup	2-85
2-45. Test Port 1 Magnitude Dynamic Accuracy Test Setup	2-88
2-46. Dynamic Accuracy (Phase)	2-91
2-47. Test Port Magnitude Compression Test Setup	2-94
2-48. Test Port Phase Compression Test Setup	2-97
2-49. Test Port Output Harmonics Test Setup	2-100
2-50. Receiver Harmonics Test Setup	2-101
2-51. Test Port Output Harmonics Test Setup	2-105
2-52. Receiver Harmonics Test Setup	2-107
3-1. Partial Component Location Diagram	3-6
3-2. RF Output Correction Constants Test Setup for the HP 8753D	3-12
3-3. Maximum Intensity Adjustment Setup	3-17
3-4. First Connections for Insertion Loss Measurement	3-23
3-5. Second Connections for Insertion Loss Measurement	3-24
3-6. Connections for Sampler Correction Routine	3-25
3-7. Connections for Sampler Correction at 6 GHz	3-26
3-8. Connections for Sampler Correction at Port 2	3-27
3-9. Connections for Sampler Correction at Port 2 for 6 GHz	3-28
3-10. Connections for the Second Thru Cable	3-28
3-11. Setup for Cavity Oscillator Frequency Correction Constant Routine	3-32
3-12. Typical Display of Spurs with a Filter	3-33
3-13. Typical Display of Four Spurs without a Filter	3-34
3-14. Target Spur Is Fourth in Display of Five Spurs	3-35
3-15. Target Spur Is Almost Invisible	3-36
3-16. Vertical Position and Focus Adjustment Locations	3-45
3-17. Location of the FN VCO TUNE Adjustment	3-48
3-18. Fractional-N Frequency Range Adjustment Display	3-48
3-19. Frequency Accuracy Adjustment Setup	3-51
3-20. Location of the VCXO ADJ Adjustment	3-52

Contents-18

3-21. High Stability Frequency Adjustment Location	3-53
3-22. High/Low Band Transition Adjustment Trace	3-55
3-23. High/Low Band Adjustment Locations	3-55
3-24. Fractional N Spur Avoidance and FM Sideband Adjustment Setup	3-57
3-25. Location of API and 100 kHz Adjustments	3-58
3-26. Location of A11 Test Points and A3 CAV ADJ Adjustments . . .	3-60
3-27. Display of Acceptable versus Excessive Spikes	3-61
4-1. Preset Sequence	4-3
4-2. Operator's Check Setup	4-4
4-3. Troubleshooting Organization	4-8
4-4. A15 Preregulator LEDs	4-9
4-5. Front Panel Power Up Sequence	4-10
4-6. Equipment Setup for Source Power Check	4-13
4-7. ABUS Node 16: 1V/GHz	4-14
4-8. Equipment Setup	4-15
4-9. Typical Measurement Trace	4-16
4-10. HP 8753D Overall Block Diagram	4-19
5-1. Power Supply Group Simplified Block Diagram	5-3
5-2. Location of A15 Diagnostic LEDs	5-4
5-3. A8 Post Regulator Test Point Locations	5-5
5-4. Removing the Line Fuse	5-7
5-5. Power Supply Cable Locations	5-9
5-6. A15W1 Plug Detail	5-10
5-7. Front Panel Probe Power Connector Voltages	5-19
5-8. Power Supply Block Diagram	5-23
6-1. Digital Control Group Block Diagram	6-3
6-2. Jumper Positions on the A9 CPU	6-4
6-3. CPU LED Window on Rear Panel	6-5
6-4. Preset Sequence	6-8
6-5. Pin Locations on A19J5	6-13
6-6. Pin Locations on Connector of W14	6-14
6-7. A9 CPU Walking One Pattern	6-15
6-8. Pin Locations on Connector of W20	6-16
7-1. Basic Phase Lock Error Troubleshooting Equipment Setup . . .	7-4
7-2. Jumper Positions on the A9 CPU	7-5
7-3. Sampler/Mixer to Phase Lock Cable Connection Diagram . . .	7-6
7-4. Waveform Integrity in SRC Tune Mode	7-8
7-5. Phase Locked Output Compared to Open Loop Output in SRC Tune Mode	7-9
7-6. 1V/GHz at Analog Bus Node 16 with Source PLL Off.	7-10

7-7. YO- and YO+ Coil Drive Voltage Differences with SOURCE PLL OFF	7-11
7-8. Sharp 100 kHz Pulses at A13TP5 (any frequency)	7-15
7-9. High Band REF Signal (\geq 16 MHz CW)	7-16
7-10. REF Signal at A11TP9 (5 MHz CW)	7-17
7-11. Typical FN LO Waveform at A12J1	7-18
7-12. 4 MHz Reference Signal at A12TP9 (Preset)	7-19
7-13. 90 Degree Phase Offset of High Band 2nd LO Signals (\geq 16 MHz CW)	7-20
7-14. In-Phase Low Band 2nd LO Signals (14 MHz CW)	7-21
7-15. L ENREF Line at A12P2-16 (Preset)	7-22
7-16. Complementary L HB and L LB Signals (Preset)	7-23
7-17. 10 MHz HI OUT Waveform from A14J1	7-25
7-18. 25 MHz HI OUT Waveform from A14J1	7-25
7-19. 60 MHz HI OUT Waveform from A14J1	7-26
7-20. LO OUT Waveform at A14J2	7-27
7-21. A14 Generated Digital Control Signals	7-29
7-22. H MB Signal at A14P1-5 (Preset and 16 MHz to 31 MHz Sweep) .	7-30
7-23. Pulse Generator Output	7-31
7-24. High Quality Comb Tooth at 3 GHz	7-32
7-25. Stable HI OUT Signal in FRACN TUNE Mode	7-33
7-26. Typical 1st IF Waveform in FRACN TUNE/SRC TUNE Mode .	7-34
7-27. FM Coil – Plot with 3 Point Sweep	7-36
8-1. Equipment Setup	8-4
8-2. Typical Good Trace	8-5
8-3. 4 MHz REF Waveform	8-7
8-4. Digital Data Lines Observed Using L INTCOP as Trigger . . .	8-10
8-5. Digital Control Lines Observed Using L INTCOP as Trigger .	8-10
8-6. 2nd IF (4 kHz) Waveform	8-12
8-7. Typical Trace with Sampler Correction On and Off	8-13
9-1. Typical Return Loss Traces of Good and Poor Cables	9-5
9-2. Typical Smith Chart Traces of Good Short (a) and Open (b) .	9-7
10-1. Internal Diagnostics Menus	10-2
10-2. Jumper Positions on the A9 CPU	10-8
10-3. Service Feature Menus	10-18
10-4. Analog Bus Node 1	10-27
10-5. Analog Bus Node 2	10-28
10-6. Analog Bus Node 3	10-29
10-7. Analog Bus Node 4	10-30
10-8. Analog Bus Node 6	10-31
10-9. Analog Bus Node 7	10-32

10-10. Analog Bus Node 14	10-35
10-11. Analog Bus Node 15	10-36
10-12. Analog Bus Node 16	10-37
10-13. Counter Readout Location	10-38
10-14. Analog Bus Node 18	10-39
10-15. Analog Bus Node 20	10-40
10-16. Analog Bus Node 23	10-41
10-17. Analog Bus Node 29	10-44
10-18. Analog Bus Node 30	10-45
10-19. Location of Firmware Revision Information on Display	10-47
11-1. Standard Connections for Full Two-Port Error-Correction	11-3
11-2. Typical EDF/EDR without and with Cables	11-10
11-3. Typical ESF/ESR without and with Cables	11-11
11-4. Typical ERF/ERR without and with Cables	11-12
11-5. Typical EXF/EXR with 10 Hz Bandwidth and with 3 kHz Bandwidth	11-13
11-6. Typical ELF/ELR	11-14
11-7. Typical ETF/ETR	11-15
12-1. Simplified Block Diagram of the Network Analyzer System	12-2
12-2. Power Supply Functional Group, Simplified Block Diagram	12-5
12-3. Digital Control Group, Simplified Block Diagram	12-9
12-4. Low Band Operation of the Source	12-16
12-5. High Band Operation of the Source	12-19
12-6. Harmonic Analysis	12-22
12-7. External Source Mode	12-23
12-8. Tuned Receiver Mode	12-24
12-9. Simplified Block Diagram of the Built-in Test Set	12-26
12-10. Receiver Functional Group, Simplified Block Diagram	12-27
13-1. Module Exchange Procedure	13-4

Tables

1-1. Required Tools	1-1
1-2. Service Test Equipment	1-2
1-3. Connector Care Quick Reference	1-5
2-1. Magnitude Dynamic Accuracy Calculations	2-84
3-1. Related Service Procedures	3-3
5-1. A8 Post Regulator Test Point Voltages	5-6
5-2. Output Voltages	5-10
5-3. Recommended Order for Removal/Disconnection	5-12
5-4. Recommended Order for Removal/Disconnection	5-18
6-1. LED Code and Pattern Versus Test Failed	6-6
6-2. Front Panel Key Codes	6-9
6-3. Internal Diagnostic Test with Commentary	6-12
7-1. Output Frequency in SRC Tune Mode	7-8
7-2. Analog Bus Check of Reference Frequencies	7-12
7-3. A12 Reference Frequencies	7-14
7-4. A12-Related Digital Control Signals	7-22
7-5. VCO Range Check Frequencies	7-24
7-6. A14-to-A13 Digital Control Signal Locations	7-29
7-7. 1st IF Waveform Settings	7-34
7-8. A11 Input Signals	7-35
8-1. Signals Required for A10 Assembly Operation	8-9
8-2. 2nd IF (4 kHz) Signal Locations	8-11
8-3. 2nd LO Locations	8-14
9-1. Components Related to Specific Error Terms	9-4
10-1. Test Status Terms	10-4
10-2. Descriptions of Jumper Positions	10-8
11-1. Calibration Coefficient Terms and Tests	11-6
11-2. Uncorrected System Performance of HP 8753D (50Ω) with 7 mm Test Ports	11-8
12-1. Super Low Band Subsweep Frequencies	12-14
12-2. Low Band Subsweep Frequencies	12-17
12-3. High Band Subsweep Frequencies	12-20
12-4. Mixer Frequencies	12-29

13-1. Reference Designations, Abbreviations, and Options	13-46
14-1. Related Service Procedures	14-60
15-1. Hewlett-Packard Sales and Service Offices	15-3

Service Equipment and Analyzer Options

Table of Service Test Equipment

Table 1-1. Required Tools

T-8, T-10, T-15 and T-20 TORX screwdrivers
Flat-blade screwdrivers—small, medium, and large
5/16-inch open-end wrench (for SMA nuts)
3/16, 5/16, and 9/16-inch hex nut drivers
5/16-inch open-end torque wrench (set to 10 in-lb)
2.5-mm hex-key driver
Non-conductive and non-ferrous adjustment tool
Needle-nose pliers
Tweezers
Antistatic work mat with wrist-strap

Table 1-2. Service Test Equipment

Required Equipment	Critical Specifications	Recommended Model	Use*
Spectrum Analyzer	Freq. Accuracy ± 7 Hz	HP 8563E	A, T
Frequency Counter		HP 5350B	P
Source		HP 83640A	P
Oscilloscope	Bandwidth: 100 MHz Accuracy: 10%	any	T
Digital Voltmeter	Resolution: 10 mV	any	T
Tool Kit	No substitute	HP part number 08753-60023	T
Power Meter (HP-IB)	No substitute	HP 437A or 438A	A, P, T
Power Sensor	Frequency: 300 kHz-3 GHz, 50Ω	HP 8482A	A, P, T
Power Sensor (for Option 006)	Frequency: 3 GHz-6 GHz	HP 8481A	A, P, T
Power Sensor	Frequency: 300 kHz-3 GHz, 75Ω	HP 8483A Opt. H03	P
Photometer		Tektronix J16	A
Photometer Probe		Tektronix J6503	A
Light Occluder		Tektronix 016-0305-00	A
CRT Demagnetizer or Bulk Tape Eraser			A
Printer		HP ThinkJet, DeskJet, LaserJet	P
Floppy Disk	3.5-inch	HP 92192A	A
Calibration Kit 7 mm, 50Ω	No substitute	HP 85031B	P
Calibration Kit Type-N, 75Ω	No substitute	HP 85036B	P
Verification Kit 7 mm	No substitute	HP 85029B	P
Low Pass Filter	>50 dB @ 2.96 Hz and passband that includes 800 MHz	HP P/N 9135-0198	A
Step Attenuator	110 dB (Calibrated @ 30 MHz)	HP 8496A	P
Attenuators (fixed):	Return loss: ≥ 32 dB APC-7 20 dB (2)	HP 8492A Opt. 020	P, T
Power Splitter	2-Way, 50Ω	HP 11667A	P, T
Minimum Loss Pad	Type-N, 50Ω to 75Ω	HP 11853B	P, T

1-2 Service Equipment and Analyzer Options

Table 1-2. Service Test Equipment (2 of 2)

Required Equipment	Critical Specifications	Recommended Model	Use*
Adapter	APC-7 to Type-N (f)	HP 11524A	A, P
Adapter	APC-7 to Type-N (m)	HP 11525A	A, P
Adapter	APC-7 to 3.5 mm (m)	HP P/N 1250-1746	A, P
Adapter	APC-7 to 3.5 mm (f)	HP P/N 1250-1747	A
Adapter	BNC to Alligator Clip	HP P/N 8120-1292	A
Adapter	APC-3.5 (m) to Type-N (f)	HP P/N 1250-1750	A, P
Adapter	APC-3.5 (f) to Type-N (f)	HP P/N 1250-1745	A, P
Adapter	BNC (m) to Type-N (f)	HP P/N 1250-1477	P
Adapter	Type-N (m) to Type-N (m)	HP P/N 1250-1528	P
RF Cable (2 each)	24-inch, APC-7	HP P/N 8120-4779	A, P
RF Cable Set	APC-7	HP 11857D	A, P
RF Cable	APC-7, 50Ω	HP 11857D	P
RF Cable	24-inch, APC-7, 50Ω	HP P/N 8120-4779	P
RF Cable	24-inch, Type-N, 75Ω	HP P/N 8120-2408	A, P
RF Cable	24-inch, Type-N, 50Ω	HP P/N 8120-4781	A, P
RF Cable Set	Type-N, 50Ω	HP 11851B	P
HP-IB Cable		HP 10833A/B/C/D	A
Coax Cable	BNC	HP P/N 8120-1840	A
Coax Cable	BNC (m) to BNC (m), 50Ω	HP 10503A	A
Antistatic Wrist Strap		HP P/N 9300-1367	A, T, P
Antistatic Wrist Strap Cord		HP P/N 9300-0980	A, T, P
Static-control Table Mat and Earth Ground Wire		HP P/N 9300-0797	A, T, P

* P - Performance Tests

A - Adjustment

T - Troubleshooting

Principles of Microwave Connector Care

Proper connector care and connection techniques are critical for accurate, repeatable measurements.

Refer to the calibration kit documentation for connector care information. Prior to making connections to the network analyzer, carefully review the information about inspecting, cleaning and gaging connectors.

Having good connector care and connection techniques extends the life of these devices. In addition, you obtain the most accurate measurements.

This type of information is typically located in Chapter 3 of the calibration kit manuals.

For additional connector care instruction, contact your local Hewlett-Packard Sales and Service Office about course numbers HP 85050A+24A and HP 85050A+24D.

See the following table for quick reference tips about connector care.

Table 1-3. Connector Care Quick Reference

Handling and Storage	
Do	Do Not
Keep connectors clean	Touch mating-plane surfaces
Extend sleeve or connector nut	Set connectors contact—end down
Use plastic end-caps during storage	
Visual Inspection	
Do	Do Not
Inspect all connectors carefully	Use a damaged connector—ever
Look for metal particles, scratches, and dents	
Connector Cleaning	
Do	Do Not
Try compressed air first	Use any abrasives
Use isopropyl alcohol	Get liquid into plastic support beads
Clean connector threads	
Gaging Connectors	
Do	Do Not
Clean and zero the gage before use	Use an out-of-spec connector
Use the correct gage type	
Use correct end of calibration block	
Gage all connectors before first use	
Making Connections	
Do	Do Not
Align connectors carefully	Apply bending force to connection
Make preliminary connection lightly	Over tighten preliminary connection
Turn only the connector nut	Twist or screw any connection
Use a torque wrench for final connect	Tighten past torque wrench “break” point

Analyzer Options Available

Option 1D5, High Stability Frequency Reference

This option offers ± 0.05 ppm temperature stability from 0 to 60 °C (referenced to 25 °C).

Option 002, Harmonic Mode

This option provides measurement of second or third harmonics of the test device's fundamental output signal. Frequency and power sweep are supported in this mode. Harmonic frequencies can be measured up to the maximum frequency of the receiver. However, the fundamental frequency may not be lower than 16 MHz.

Option 006, 6 GHz Operation

This option extends the maximum source and receiver frequency of the analyzer to 6 GHz.

Option 010, Time Domain

This option displays the time domain response of a network by computing the inverse Fourier transform of the frequency domain response. It shows the response of a test device as a function of time or distance. Displaying the reflection coefficient of a network versus time determines the magnitude and location of each discontinuity. Displaying the transmission coefficient of a network versus time determines the characteristics of individual transmission paths. Time domain operation retains all accuracy inherent with the correction that is active in of such devices as SAW filters, SAW delay lines, RF cables, and RF antennas.

Option 011, Receiver Configuration

This option allows front panel access to the R, A, and B samplers and receivers. The transfer switch, couplers, and bias tees have been removed. Therefore, external accessories are required to make most measurements.

Option 075, 75Ω Impedance

This option offers 75Ω impedance bridges with type-N test port connectors.

Option 1CM, Rack Mount Flange Kit Without Handles

This option is a rack mount kit containing a pair of flanges and the necessary hardware to mount the instrument, with handles detached, in an equipment rack with 482.6 mm (19 inches) horizontal spacing.

Option 1CP, Rack Mount Flange Kit With Handles

This option is a rack mount kit containing a pair of flanges and the necessary hardware to mount the instrument with handles attached in an equipment rack with 482.6 mm (19 inches) spacing.

Service and Support Options

The analyzer automatically includes a one-year on-site service warranty, where available. If on-site service is not available in your local area, you can purchase the HP 8753D with a W08 option, which converts the one year on-site warranty to a three year return to HP warranty. Consult your local Hewlett-Packard sale engineer for availability of on-site service.

The following service and support options are available at the time you purchase an HP 8753D network analyzer.

Option W31

This option adds two years of on-site repair to the product warranty, providing three years of repair coverage.

Option W51

This option adds four years of on-site repair to the product warranty, providing five years of repair coverage.

Option W32

This option provides three years of return to HP calibration service.

Option W52

This option provides five years of return to HP calibration service.

Option W34

This option provides three years of return to HP Standards Compliant Calibration.

Option W54

This option provides five years of return to HP Standards Compliant Calibration.

If support was not purchased along with the analyzer, there are many repair and calibration options available from Hewlett-Packard's support organization. These options cover a range of on-site services and agreements with varying response times as well as return to HP agreements and per-incident pricing. Contact your local Hewlett-Packard customer engineer for details.

2

System Verification and Performance Tests

This chapter describes the system verification and performance tests for your network analyzer. System verification involves two-port calibration of the analyzer and the measurement of several devices that comprise a verification kit. The successful completion of the system verification tests confirms that the analyzer is making correct measurements within measurement uncertainties on devices whose behaviors have been characterized by Hewlett-Packard. The performance tests confirm the analyzer's technical specifications and involve testing the performance of individual subsystems of the analyzer such as the source and receiver. Successful completion of the performance tests assures that the analyzer is performing to specifications.

How to Test the Performance of Your Analyzer

To obtain the same quality of performance testing that Hewlett-Packard has administered at the factory, you must perform:

- the system verification procedure

AND

- *all* of the performance test procedures.

This quality of performance testing guarantees that the analyzer is performing within *all* of the published specifications. Hewlett-Packard will issue a Certificate of Calibration for your analyzer if two conditions are met:

1. Your analyzer passes all the performed tests.
2. The equipment and standards that you used to perform the tests are traceable to a national standards institute.

Note

If you have a particular type of measurement application that does not use all of the analyzer's measurement capabilities, you may ask your local Hewlett-Packard Customer Service Center for a subset of specifications that you want verified. However, this does create a potential for making incorrect measurements by using a different application than what was specified.

Sections in this Chapter

- **System Verification**

- Automated Mode
- Manual Mode

- **Performance Tests**

1. Test Port Output Frequency Range and Accuracy
2. External Source Mode Frequency Range
3. Test Port Output Power Accuracy
4. Test Port Output Power Range and Linearity
5. Minimum R Channel Level
6. Test Port Input Noise Floor Level
7. Test Port Input Frequency Response

2-2 System Verification and Performance Tests

8. Test Port Crosstalk
9. Calibration Coefficients
10. System Trace Noise (Only for Analyzers *without* Option 006)
11. System Trace Noise (Only for Analyzers *with* Option 006)
12. Test Port Input Impedance
13. Test Port Receiver Magnitude Dynamic Accuracy
14. Test Port Receiver Phase Dynamic Accuracy
15. Test Port Receiver Magnitude Compression
16. Test Port Receiver Phase Compression
17. Test Port Output/Input Harmonics (Option 002 Analyzers *without* Option 006 only)
18. Test Port Output/Input Harmonics (Option 002 Analyzers *with* Option 006 only)

Performance Test Record

Find and use the appropriate “Performance Test Record” in the following subchapters:

- 2a. Test Record for 30 kHz to 3 GHz
- 2b. Test Record for 30 kHz to 6 GHz

2-4 System Verification and Performance Tests

System Verification Cycle and Kit Re-certification

Hewlett-Packard recommends that you verify your network analyzer measurement system every six months. Hewlett-Packard also suggests that you get your verification kit re-certified annually. Refer to *HP 85029B 7 mm Verification Kit Operating and Service Manual* for more information.

Note	The system verification procedures can also apply to analyzers with Option 075 (75 ohm analyzers) if minimum loss pads and Type-N (m) to APC-7 adapters are used.
-------------	---

How to Select the System Verification Procedure

Check to see how the verification kit floppy disk is labeled:

- If the disk is labeled HP 8753D Verification Data Disk, proceed with the "HP 8753D Automated Mode System Verification."
- If the disk is labeled HP 8753 Verification Data Disk, proceed with the "HP 8753D Manual Mode System Verification" procedure, located later in this chapter.

Note	If your verification disk is not labeled HP 8753D Verification Data Disk, you may send your HP 85029B 7-mm verification kit to the nearest service center for recertification, which includes a data disk that you can use with the HP 8753D.
-------------	---

HP 8753D Automated Mode System Verification

Equipment Required

Calibration Kit, 7 mm	HP 85031B
Verification Kit, 7 mm	HP 85029B
Test Port Extension Cable Set, 7 mm	HP 11857D
Printer	HP ThinkJet/DesktopJet/LaserJet

Additional Equipment Required for Option 075 Analyzers

Minimum Loss Pad (2), 50Ω to 75Ω	HP 11852B
Adapter (2), APC-7 to Type-N (m)	HP 11525A

Analyzer warm-up time: 1 hour

This system verification consists of three separate procedures:

1. Initialization
2. Measurement Calibration
3. Device Verification

Initialization

1. Connect the equipment as shown in Figure 2-1. Let the analyzer warm up for one hour.

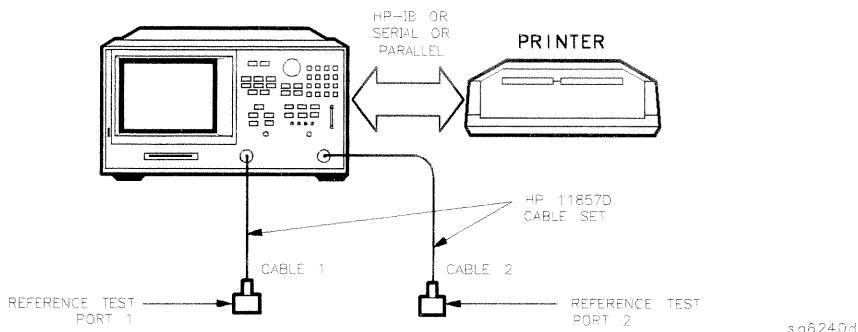


Figure 2-1. System Verification Test Setup

2. While the equipment is warming up, review the "Connector Care Quick Reference" information in the "Service Equipment and Analyzer Options"

2-6 System Verification and Performance Tests

chapter. Good connections and clean, undamaged connectors are critical for accurate measurement results.

3. Insert the verification kit disk into the analyzer disk drive.
4. Press [PRESET] [SAVE/RECALL] SELECT DISK INTERNAL DISK .
5. If you want a printout of the verification data for all the devices, press [SYSTEM] SERVICE MENU TEST OPTIONS RECORD ON .

Note If you switch on the record function, you *CANNOT* switch it off during the verification procedure.

6. Position the paper in the printer so that printing starts at the top of the page.
7. If you have difficulty with the printer:
 - If the interface on your printer is HP-IB, verify that the printer address is set to 1 (or change the setting in the analyzer to match the printer).
 - If the interface on your printer is serial or parallel, be sure that you selected the printer port and the printer type correctly (refer to the *HP 8753D Network Analyzer User's Guide* for more information on how to perform these tasks).
8. Press [SYSTEM] SERVICE MENU TESTS SYS VER TESTS EXECUTE TEST .
9. The analyzer displays Sys Ver Init DONE, the initialization procedure is complete.

Caution *DO NOT* press [PRESET] or recall another instrument state. You must use the instrument state that you loaded during the initialization procedure.

Measurement Calibration

10. Press **CAL CAL KIT SELECT CAL KIT CAL KIT:7mm RETURN RETURN CALIBRATE MENU FULL 2-PORT .**
11. Press **ISOLATION OMIT ISOLATION .**
12. Press **REFLECTION .**
13. Connect the “open” end of the open/short combination (supplied in the calibration kit) to reference test port 1, as shown in Figure 2-2.

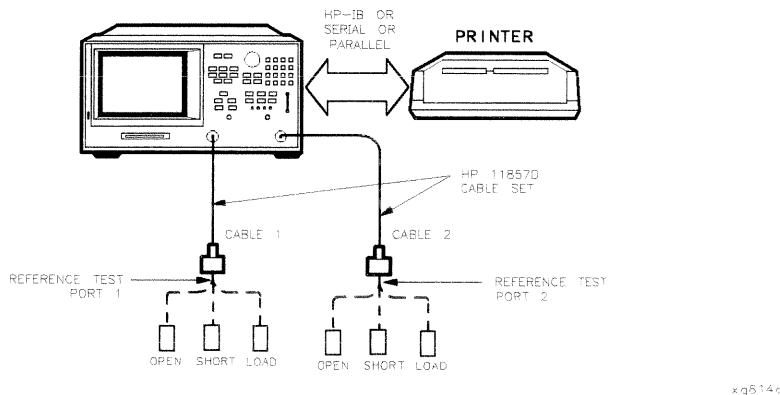


Figure 2-2. Connections for Measurement Calibration Standards

14. Press **FORWARD:OPEN .**
15. When the analyzer finishes measuring the standard, connect the “short” end of the open/short combination to reference test port 1.
16. Press **FORWARD:SHORT .**
17. When the analyzer finishes measuring the standard, connect the 50 ohm termination (supplied in the calibration kit) to reference test port 1.
18. Press **FORWARD:LOAD .**
19. When the analyzer finishes measuring the standard, connect the “open” end of the open/short combination to reference test port 2.

2-8 System Verification and Performance Tests

20. Press REVERSE:OPEN .
21. When the analyzer finishes measuring the standard, connect the “short” end of the open/short combination to reference test port 2.
22. Press REVERSE:SHORT .
23. When the analyzer finishes measuring the standard, connect the 50 ohm termination to reference test port 2.
24. Press REVERSE:LOAD .
25. When the analyzer finishes measuring the standard, press STANDARDS DONE .
The analyzer briefly displays COMPUTING CAL COEFFICIENTS.
26. Connect the test port cables as shown Figure 2-3.

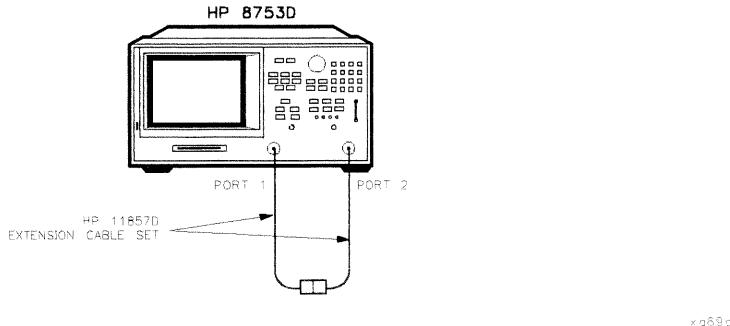


Figure 2-3. Transmission Calibration Setup

27. Press TRANSMISSION DO BOTH FWD + REV .
28. Press DONE 2-PORT CAL .
29. Press [SAVE/RECALL] SELECT DISK INTERNAL MEMORY RETURN SAVE STATE to save the calibration into the analyzer internal memory.
30. When the analyzer finishes saving the instrument state, press SELECT DISK INTERNAL DISK .

**System Verification and 2-9
Performance Tests**

Device Verification

31. Press **SYSTEM SERVICE MENU TESTS** [28] **x1 EXECUTE TEST**.
32. At the prompt, connect the 20 dB attenuator (supplied in the verification kit) as shown in Figure 2-4.
33. Press **CONTINUE** to run the test:
 - If you switched OFF the record function, you have to press **CONTINUE** after each S-parameter measurement.
 - If you switched ON the record function, the analyzer measures all S-parameters (magnitude and phase) without pausing. Also, the analyzer only displays and prints the PASS/FAIL information for the S-parameter measurements that are valid for system verification.

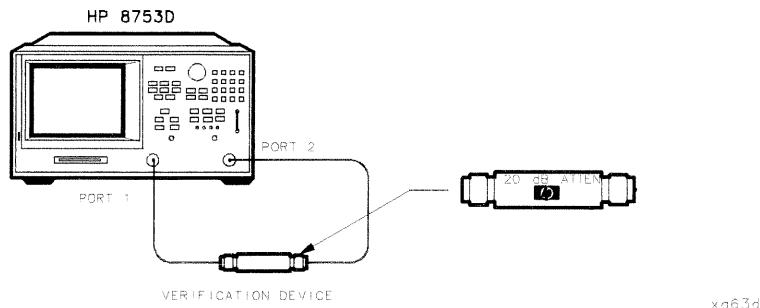


Figure 2-4. Connections for the 20 dB Verification Device

34. When the analyzer finishes all the measurements, connect the 50 dB attenuator (supplied in the verification kit), as shown in Figure 2-5.

2-10 System Verification and Performance Tests

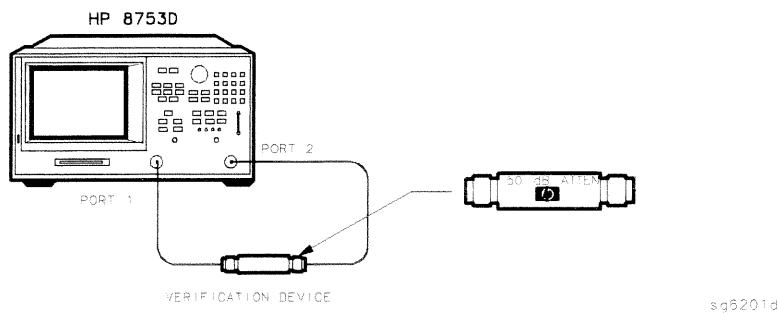


Figure 2-5. Connections for the 50 dB Verification Device

35. Press **UP** **29** **x1** EXECUTE TEST CONTINUE.
36. When all measurements are complete, replace the verification device with the verification mismatch, as shown in Figure 2-6. Be sure that you connect Port A of the verification mismatch to reference test port 1.

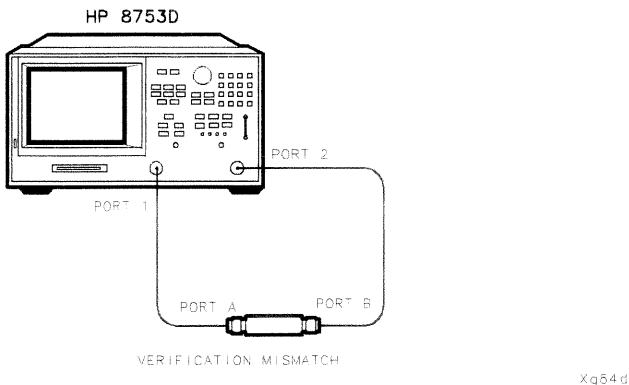


Figure 2-6. Mismatch Device Verification Setup

37. Press RETURN TESTS **30** **x1** EXECUTE TEST CONTINUE.
38. When the analyzer finishes all the measurements, connect the mismatch verification device, as shown in Figure 2-7. Notice that Port B is now connected to reference test port 1.

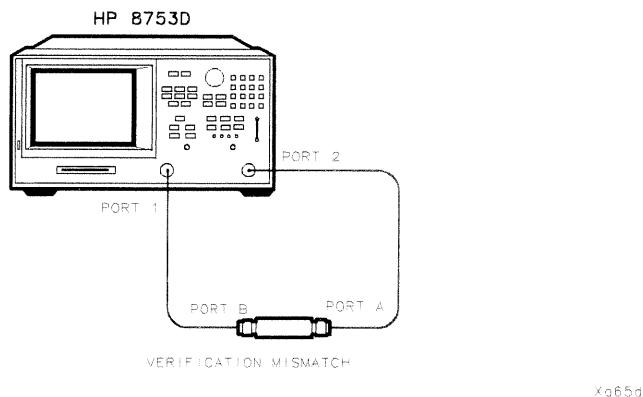


Figure 2-7. Mismatch Device Verification Setup

39. Press RETURN TESTS [31] [x1] EXECUTE TEST CONTINUE.
40. You have completed the system verification procedure when the analyzer displays Ver Def 4 DONE.

2-12 System Verification and Performance Tests

In Case of Difficulty

1. Inspect all connections. *DO NOT* disconnect the cables from the analyzer test ports. Doing so *WILL INVALIDATE* the calibration that you have done earlier.
2. Press [PRESET] [SAVE/RECALL] SELECT DISK INTERNAL MEMORY RETURN .
Using the front panel knob, highlight the title of the full 2-Port calibration that you have done earlier, then press RECALL STATE .
3. Repeat the “Device Verification” procedure.
4. If the analyzer still fails the test, check the measurement calibration as follows:
 - a. Press [PRESET].
 - b. Recall the calibration by pressing [SAVE/RECALL] SELECT DISK INTERNAL MEMORY RETURN .
 - c. Use the front panel knob to highlight the calibration you want to recall and press RECALL STATE .
 - d. Connect the short to reference test port 1.
 - e. Press [MEAS] Ref1: FWD S11 (A/R) [MENU] TRIGGER MENU CONTINUOUS .
 - f. Press [SCALE REF] SCALE/DIV (.05) (x1).
 - g. Check that the trace response is 0.00 ± 0.05 dB.
 - h. Disconnect the short and connect it to reference test port 2.
 - i. Press [MEAS] Ref1: REV S22(B/R) .
 - j. Check that the trace response is 0.00 ± 0.05 dB.
 - k. If any of the trace responses are out of the specified limits, repeat the “Measurement Calibration” and “Device Verification” procedures.
5. Refer to the “Start Troubleshooting Here” chapter for more troubleshooting information.

HP 8753D Manual Mode System Verification

Equipment Required

Calibration Kit, 7 mm	HP 85031B
Verification Kit, 7 mm	HP 85029B
Test Port Extension Cable Set, 7 mm	HP 11857D
Printer	HP ThinkJet/DesktopJet/LaserJet

Additional Equipment Required for Option 075 Analyzers

Minimum Loss Pad (2), 50Ω to 75Ω	HP 11852B
Adapter (2), APC-7 to Type-N (m)	HP 11525A

Analyzer warm-up time: 1 hour

This system verification consists of three separate procedures:

1. Initialization
2. Measurement Calibration
3. Device Verification

Initialization

1. Connect the equipment as shown in Figure 2-8. Let the analyzer warm up for one hour.

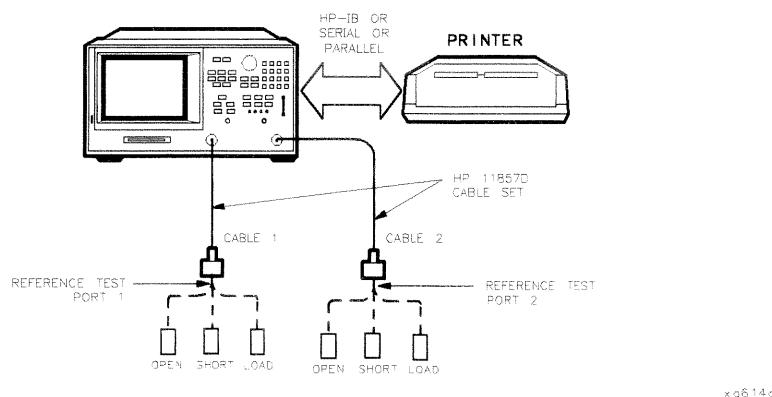


Figure 2-8. System Verification Test Setup

2-14 System Verification and Performance Tests

2. While the equipment is warming up, review the "Connector Care Quick Reference" information in the "Service Equipment and Analyzer Options" chapter. Good connections and clean, undamaged connectors are critical for accurate measurement results.
3. Set up the system to print the verification data:
 - a. Press **LOCAL SYSTEM CONTROLLER**.
 - b. Press **SET ADDRESSES PRINTER PORT**.
 - c. Press the softkey that corresponds to your printer port.
 - d. If you have difficulty with the printer:
 - If the interface on your printer is HP-IB, verify that the printer address is set to 1.
 - If the interface on your printer is serial or parallel, be sure that you correctly selected the printer port AND printer type (refer to the *HP 8753D Network Analyzer User's Guide* for more information on how to do these tasks).
4. Insert the verification kit disk into the analyzer disk drive.
5. Press **PRESET SAVE/RECALL SELECT DISK INTERNAL DISK**.
6. Press **SYSTEM SERVICE MENU TESTS SYS VER TESTS EXECUTE TEST**.
7. When the analyzer displays **Sys Ver Init DONE**, the test is complete.

Caution Do *NOT* press **PRESET** or recall another instrument state. You must use the instrument state that you loaded during the initialization procedure.

Measurement Calibration

8. Press **MENU POWER \square_2 \times_1** to set the analyzer test port power to -2 dBm.
9. Press **CAL CAL KIT:7mm RETURN CALIBRATE MENU FULL 2-PORT**.
10. Press **ISOLATION OMIT ISOLATION**.
11. Press **REFLECTION**.

12. Connect the “open” end of the open/short combination (supplied in the calibration kit) to reference test port 1, as shown in Figure 2-8.
13. Press FORWARD:OPEN .
14. When the analyzer finishes measuring the standard, connect the “short” end of the open/short combination to reference test port 1.
15. Press FORWARD:SHORT .
16. When the analyzer finishes measuring the standard, connect the 50 ohm termination (supplied in the calibration kit) to reference test port 1.
17. Press FORWARD:LOAD .
18. When the analyzer finishes measuring the standard, connect the “open” end of the open/short combination to reference test port 2, as shown in Figure 2-8.
19. Press REVERSE:OPEN .
20. When the analyzer finishes measuring the standard, connect the “short” end of the open/short calibration standard to reference test port 2.
21. Press REVERSE:SHORT .
22. When the analyzer finishes measuring the standard, connect the 50 ohm termination to reference test port 2.
23. Press REVERSE: LOAD .
24. When the analyzer finishes measuring the standard, press STANDARDS DONE .
25. Connect the test port cables together as shown in Figure 2-9.

2-16 System Verification and Performance Tests

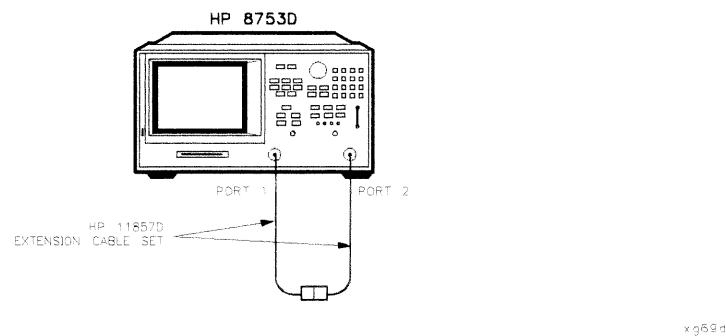


Figure 2-9. Transmission Calibration Setup

26. Press TRANSMISSION DO BOTH FWD + REV.
27. Press DONE 2-PORT CAL.
28. Press **SAVE/RECALL** SELECT DISK INTERNAL MEMORY RETURN
SAVE STATE to save the measurement calibration into the analyzer internal memory.
29. Press SELECT DISK INTERNAL DISK.

Device Verification

30. Press **SYSTEM** SERVICE MENU TESTS **[28]** **[x1]** EXECUTE TEST.
31. Connect the 20 dB attenuator (supplied in the verification kit) as shown in Figure 2-10.

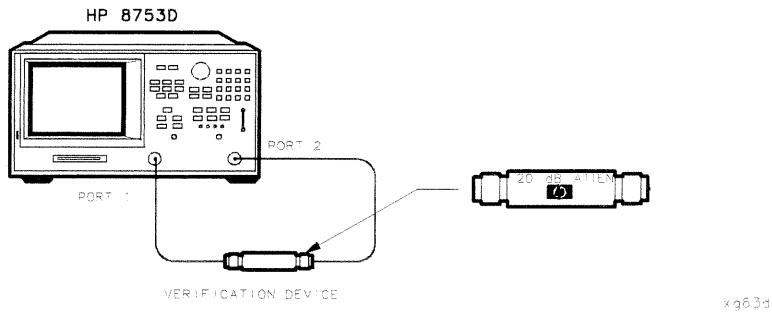


Figure 2-10. Connections for the 20 dB Verification Device

32. Press **CONTINUE** to run the test.

Ignore the error message **CAUTION: CALIBRATION REQUIRED**.

33. Press **MENU POWER -2 x1 CAL CORRECTION ON**.

34. Press **COPY PRINT MONOCHROME** to obtain the graphical representation of the measurement.

35. Press **COPY LIST PRINT ALL MONOCHROME** if you prefer a tabular representation of the measurement.

36. Press **SYSTEM SERVICE MENU TEST OPTIONS CONTINUE TEST**.

Ignore the error message **CAUTION: CALIBRATION REQUIRED**.

37. Press **MENU POWER -2 x1 CAL CORRECTION ON**.

Note

For those S-parameter measurements with upper and lower point limits shown on the analyzer display, you will notice that when you press the **CORRECTION ON** softkey, the measurement test status changes from FAIL to PASS.

If the test status remains FAIL after you presses **CORRECTION ON**, refer to "In Case of Difficulty" at the end of this test for more troubleshooting information.

38. Repeat steps 34 through 37 until you have made all the S-parameter measurements for the verification device.

2-18 System Verification and Performance Tests

Note

For each verification device, there are a total of eight measurements (magnitude and phase for the four S-parameters).

39. When the analyzer displays Ver Dev 1 FAIL, proceed to the next step only if ALL the tested S-parameter measurements show a PASS status after you activate error correction in step 37. Otherwise, refer to "In Case of Difficulty" at the end of this procedure.
40. Connect the 50 dB attenuator (supplied in the verification kit) as shown in Figure 2-11.

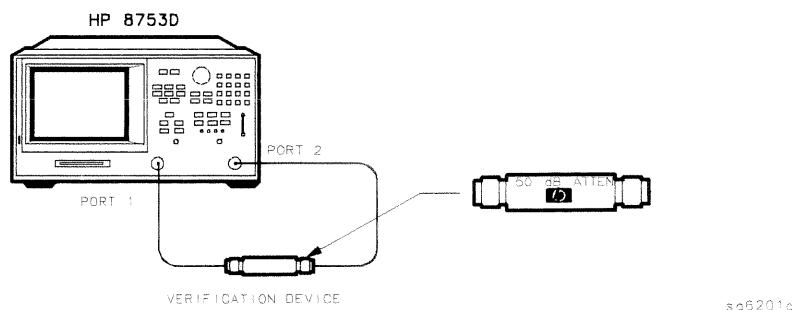


Figure 2-11. Connections for the 50 dB Verification Device

41. Press TESTS [29] EXECUTE TEST CONTINUE. Ignore the error message.
42. Press MENU POWER [-2] CAL CORRECTION ON.
43. Repeat steps 34 through 37 until you made all the S-parameter measurements for the verification device.
44. When the analyzer displays Ver Dev 2 FAIL, proceed to the next step only if *all* S-parameter measurements show a PASS status under the same condition mentioned in step 39.
45. Connect the verification mismatch (supplied in the kit) as shown in Figure 2-12. Be sure port A of the verification mismatch is connected to reference test port 1.

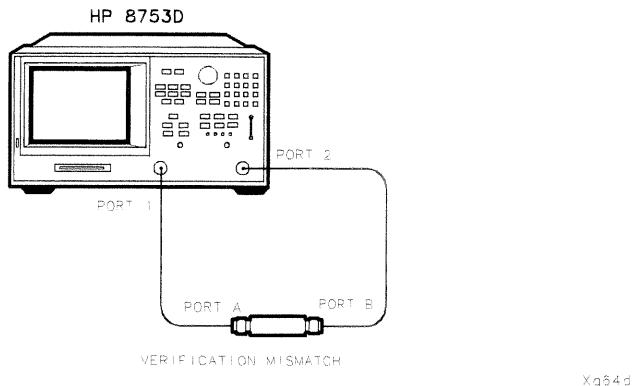


Figure 2-12. Mismatch Device Verification Setup

46. Press TESTS [30] x1 EXECUTE TEST CONTINUE .
Ignore the error message.
47. Press MENU POWER [-2] x1 CAL CORRECTION ON .
48. Repeat steps 34 through 37 until you have made all the S-parameter measurements for the verification device.
49. When the analyzer displays Ver Dev 3 FAIL proceed to the next step only if *all* S-parameter measurements show a PASS status under the same condition mentioned in step 39.
50. Connect the verification mismatch as shown in Figure 2-13. Notice that port B of the verification mismatch is now connected to the reference test port 1.

2-20 System Verification and Performance Tests

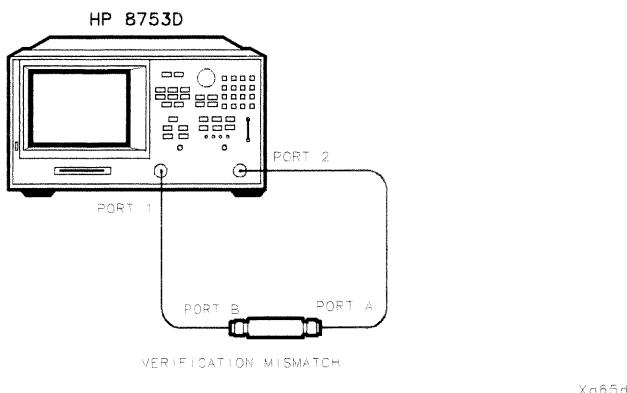


Figure 2-13. Mismatch Device Verification Setup

51. Press TESTS [31] [x1] EXECUTE TEST CONTINUE .
Ignore the displayed error message.
52. Press [MENU] POWER [-2] [x1] [CAL] CORRECTION ON .
53. Repeat steps 34 through 37 until you have made all the S-parameter measurements for the verification device.
54. The test is complete when the analyzer displays Ver Def 4 FAIL and *all* S-parameter measurements show a PASS status under the same condition mentioned in step 39.

In Case of Difficulty

1. Inspect all connections. DO NOT disconnect the cables from the analyzer test ports. Doing so WILL INVALIDATE the calibration done earlier.
2. Press [PRESET] [SAVE/RECALL] SELECT DISK INTERNAL MEMORY RETURN . Using the front panel knob, highlight the full 2-Port cal done earlier and press RECALL STATE .
3. Repeat the “Device Verification” procedure.
4. If the test still fails, do the following to check the calibration:
 - a. Press [PRESET] [SAVE/RECALL] SELECT DISK INTERNAL MEMORY RETURN .
 - b. Use the front panel knob to highlight the calibration you want to recall and press RECALL STATE .
 - c. Press [MENU] TRIGGER MENU CONTINUOUS to trigger the continuous sweeps.
 - d. Connect the short to reference test port 1.
 - e. Press [MEAS] Refl: FWD S11 (A/R) [MENU] TRIGGER MENU CONTINUOUS .
 - f. Press [SCALE REF] SCALE/DIV [.05] [x1].
 - g. Check to be sure the trace response is 0.00 ± 0.05 dB.
 - h. Disconnect the short and connect it to the reference test port 2.
 - i. Press [MEAS] Refl: REV S22(B/R) .
 - j. Check to be sure the trace response is 0.00 ± 0.05 dB.
 - k. If any of the trace responses are out of the specified limits, repeat the “Measurement Calibration” and “Device Verification” procedures.
5. Refer to the “Start Troubleshooting Here” chapter for more troubleshooting information.

1. Test Port Output Frequency Range and Accuracy Specifications

Frequency Range	Frequency Accuracy ¹
30 kHz to 3 GHz	±10 ppm
3 GHz to 6 GHz ²	±10 ppm

1 At 25 °C ±5 °C.

2 Only for analyzers with Option 006.

Required Equipment

Frequency Counter (30 kHz to 500 MHz)	HP 5350B/51B/52B
Frequency Counter (500 MHz to 6 GHz)	HP 5350B/51B/52B
Cable, 50Ω Type-N, 24-inch	HP P/N 8120-4781
Adapter, APC-3.5 (f) to Type-N (f)	HP P/N 1250-1745
Adapter, APC-7 to Type-N (f)	HP P/N 11524A
Adapter, Type-N (f) to BNC (m)	HP P/N 1250-1477

Additional equipment needed for an HP 8753D with Option 075

Minimum Loss Pad, 50Ω to 75Ω	HP 11852B
------------------------------	-----------

Analyzer warm-up time: 30 minutes

Perform this test to verify the frequency accuracy of the HP 8753D over its entire operating frequency range.

1. Connect the equipment as shown in Figure 2-14.

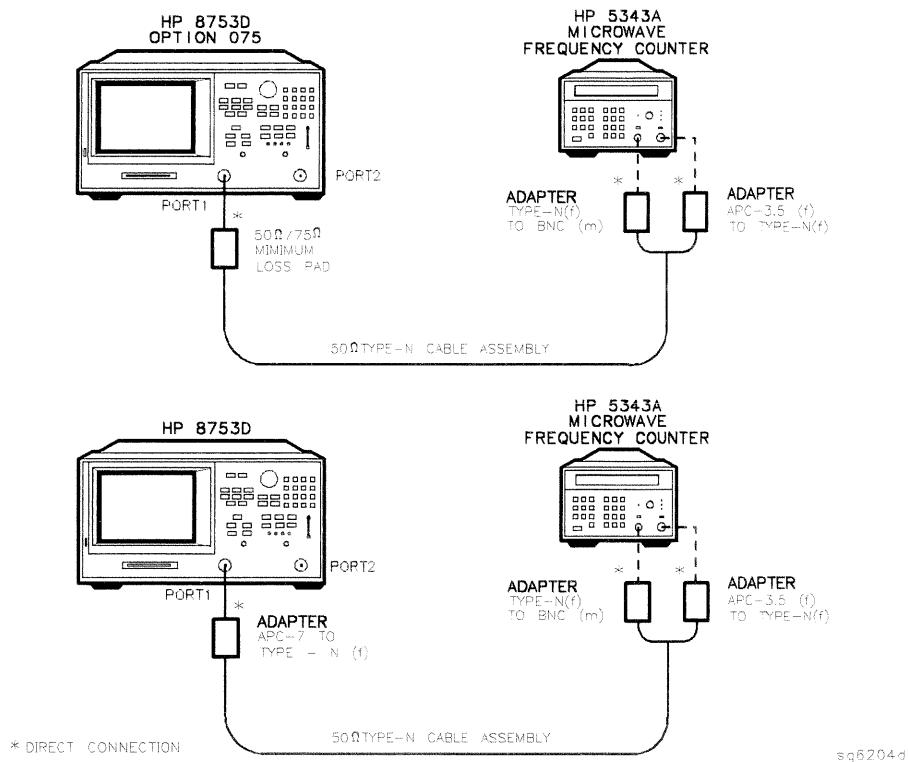


Figure 2-14. Test Port Output Frequency Range and Accuracy Test Setup

2. Press [PRESET] [MENU] CW FREQ .
3. Press [30] [k/m] and write the frequency counter reading on the "Performance Test Record."
4. Repeat step 3 for each instrument frequency listed in the "Performance Test Record."

2-24 System Verification and Performance Tests

In Case of Difficulty

1. If any measured frequency is close to the specification limits, check the time base accuracy of the counter used.
2. If the analyzer fails by a significant margin at *all* frequencies (especially if the deviation increases with frequency), the master time base probably needs adjustment. In this case, refer to the “Frequency Accuracy Adjustment” procedure, located in the “Adjustments and Correction Constants” chapter. The “Fractional-N Frequency Range Adjustment” also affects frequency accuracy.
3. Refer to the “Source Troubleshooting” chapter for related troubleshooting information.

2. External Source Mode Frequency Range Specifications

Frequency Range
30 kHz to 3 GHz
30 kHz to 6 GHz ¹

¹ Only for analyzers with Option 006.

Equipment Required

External Source HP 83640A
Cable, APC-7, 24-inch HP P/N 8120-4779
Adapter, APC-3.5 (f) to APC-7 HP P/N 1250-1747
Adapter, APC-3.5 (m) to APC-7 HP P/N 1250-1746

Analyzer warm-up time: 30 minutes

Perform this test to verify that the analyzer's reference channel, input R, is capable of phase locking to an external CW signal.

1. On the external source, press [PRESET] [CW] [10] [MHz/ μ sec] [POWER LEVEL] [–/+] [20] [GHz/dB(m)].
2. Connect the equipment as shown in Figure 2-15.

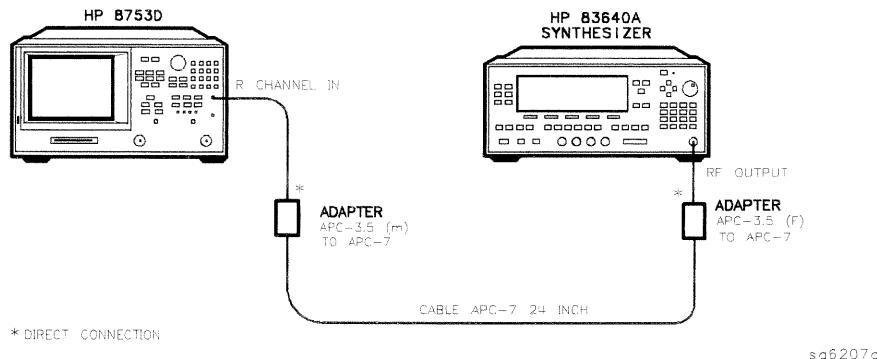


Figure 2-15. External Source Mode Frequency Range Test Setup

2-26 System Verification and Performance Tests

3. On the network analyzer, press **PRESET** **MEAS** **INPUT PORTS R**.
4. Press **SYSTEM** **INSTRUMENT MODE** **EXT SOURCE AUTO** **MENU** **CW FREQ** **10** **M/ μ** .
5. Check to see if the analyzer is phase locking to the external CW signal:
 - If the analyzer displays any phase lock error messages, write “unlock” in the “Performance Test Record” for the set CW signal.
 - If the analyzer does not display any phase lock error messages, write “lock” in the “Performance Test Record” for the set CW signal.
6. On the external source, press **CW** **20** **MHz/ μ** .
7. On the analyzer, press **20** **M/ μ** .
8. Repeat step 5 through 7 for the other external source CW frequencies listed in the “Performance Test Record.”

In Case of Difficulty

1. Be sure the external source power is set within 0 to -25 dBm.
2. Make sure the analyzer’s “Ext Source Auto” feature is selected. In addition, verify that the analyzer is set to measure its input channel R.
3. Verify that all connections are tight.

3. Test Port Output Power Accuracy

Specifications

Frequency Range	Test Port Output Power Accuracy ¹
300 kHz to 3 GHz	±1.0 dB
3 GHz to 6 GHz ²	±1.0 dB

1 At 0 dBm and 25 °C ±5 °C

2 Only for analyzers with Option 006.

Equipment Required for 50Ω Analyzers

Power Meter HP 436A/437B/438A
Power Sensor HP 8482A
Adapter, APC-7 to Type-N (f) HP 11524A

Additional Equipment Required for Analyzers with Option 006

Power Sensor HP 8481A

Equipment Required for 75Ω Analyzers

Power Meter HP 436A/437B/438A
Power Sensor HP 8483A Option H03

Analyzer warm-up time: 30 minutes

Perform this test to confirm the accuracy of the HP 8753D source output power.

1. Zero and calibrate the power meter. For more information of how to perform this task, refer to the power meter operating manual.
2. Connect the equipment as shown in Figure 2-16.

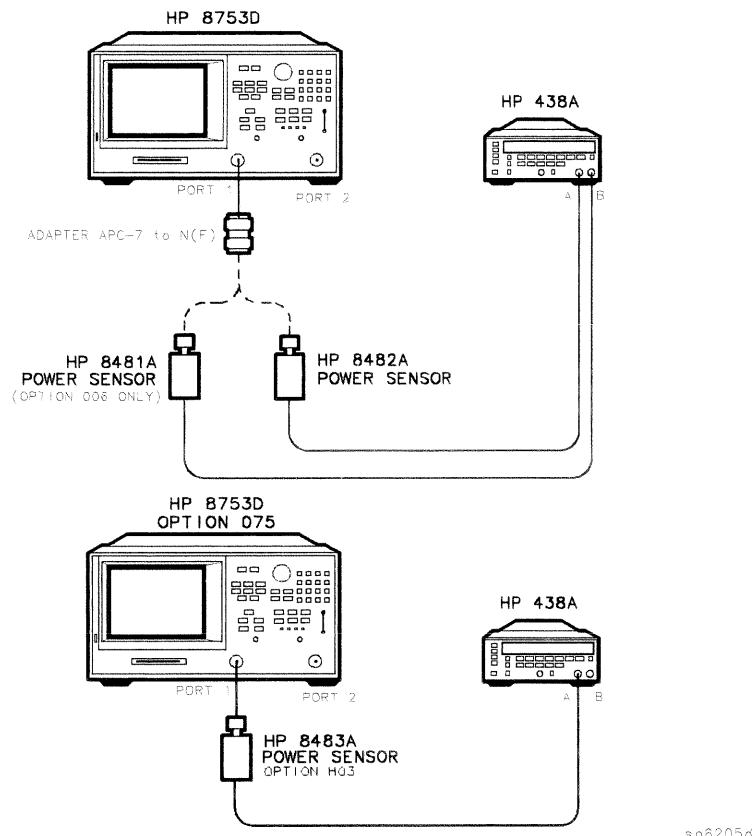


Figure 2-16. Source Output Power Accuracy Test Setup

3. Press **[PRESET]**.

Note The factory preset test port power is 0 dBm.

4. Press **[MENU] CW FREQ [300 k/m]**. Set the calibration factor on the power meter for this CW frequency.
5. Write the power meter reading on the “Performance Test Record.”
6. Repeat steps 4 and 5 for each CW frequency listed in the “Performance Test Record.” For analyzers with Option 006, use the HP 8481A power sensor for all frequencies above 3 GHz.

In Case of Difficulty

1. Be sure the source power is switched on. Press **[MENU] POWER**. Check the **SOURCE PWR** softkey, “on” *should* be highlighted. Otherwise, press **SOURCE PWR** to switch on the source power.
2. Refer to the “Source Troubleshooting” chapter for more troubleshooting information.

2-30 System Verification and Performance Tests

4. Test Port Output Power Range and Linearity

Specifications

Power Range	Power Level Linearity ¹
-15 to +5 dBm	±0.2 dB
+5 to +10 dBm	±0.5 dB

¹ Relative to 0 dBm output level.

Required Equipment

Power Meter HP 437B/438A
Power Sensor HP 8482A
Adapter, APC-7 to Type-N (f) HP 11524A

Additional Required Equipment for Analyzers with Option 006

Power Sensor HP 8481A

Additional Required Equipment for Analyzers with Option 075

Power Sensor HP 8483A Option H03

Analyzer warm-up time: 1 hour

Perform this test to verify the analyzer's test port output power range and power level linearity at selected CW frequencies.

1. Zero and calibrate the power meter. Refer to the power meter operating and service manual for more information on how to do this task.
2. On the network analyzer, press [PRESET] [MENU] CW FREQ 300 k/m. Set the power meter calibration factor for this CW frequency.
3. Connect the equipment as shown in Figure 2-17.

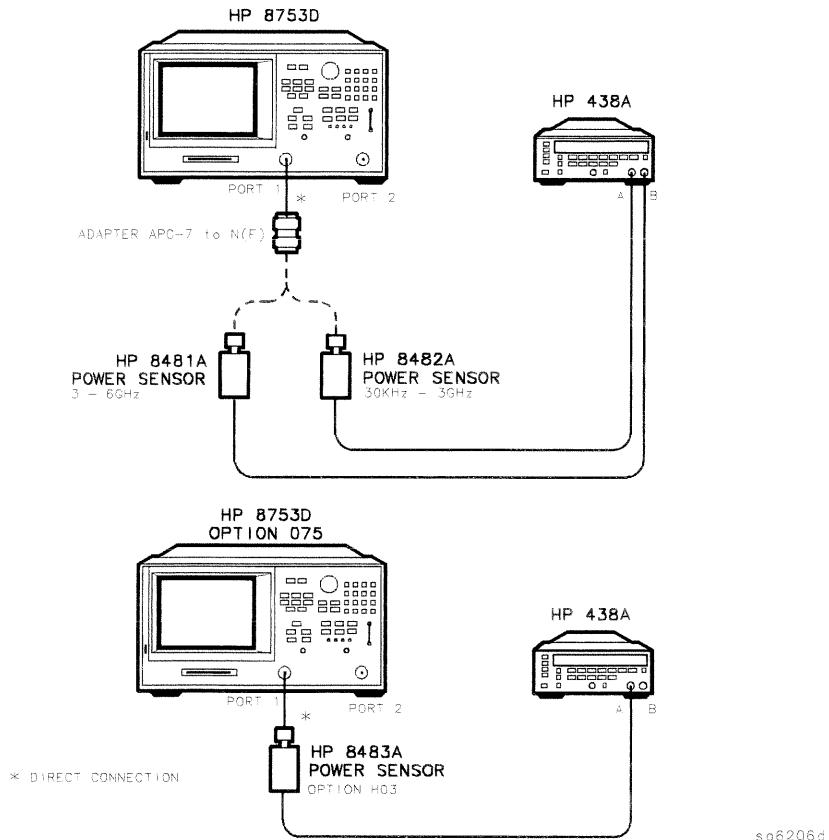


Figure 2-17. Test Port Output Power Range and Accuracy Test Setup

4. On the HP 438A, press [REL]. This sets the current power level for relative power measurement.
5. On the network analyzer, press [MENU] POWER PWR RANGE MAN .

2-32 System Verification and Performance Tests

6. Write the power meter reading in the “Results Measured” column on the “Performance Test Record.”
7. Calculate the difference between the analyzer test port power (which appears on the analyzer’s display) and the power meter reading. Write the result in the “Power Level Linearity” column on the “Performance Test Record.”
8. Repeat steps 5 through 7 for the other power levels listed in the “Performance Test Record.”
9. Press **MENU** **CW FREQ** **3** **G/n**.
10. Set the power meter calibration factor for this CW frequency and press **REL** to set the reference at this new frequency.
11. Press **MENU** **POWER** **-15** **x1**.
12. Write the power meter reading in the “Results Measured” column on the “Performance Test Record.”
13. Calculate the difference between the analyzer test port power and the power meter reading. Write the result in the “Power Level Linearity” column of the “Performance Test Record.”
14. Repeat steps 11 through 13 for the other power levels listed in the “Performance Test Record.”

In Case of Difficulty

1. Ensure that the power meter and power sensor(s) are operating to specifications. Be sure you set the power meter calibration factor for the CW frequency that you are testing.
2. Verify that there is power coming out of the analyzer’s test port 1. Be sure you did not accidentally switch off the analyzer’s internal source. If you did so, press **MENU** **POWER SOURCE PWR ON**.
3. Repeat this performance test.

5. Minimum R Channel Level

Specifications

Frequency Range	Minimum R Channel Level
300 kHz to 3 GHz	< -35 dBm
3 GHz to 6 GHz ¹	< -30 dBm

¹ Only for analyzers with Option 006.

Required Equipment for 50Ω Analyzers

Adapter, APC-3.5 (m) to APC-7 HP P/N 1250-1746
Cable, APC-7 24-inch HP P/N 8120-4779

Required Equipment for 75Ω Analyzers (Option 075)

Minimum Loss Pad, 50Ω to 75Ω HP 11852B
Cable, 50Ω Type-N, 24-inch HP P/N 8120-4781
Adapter, APC-3.5 (m) to Type-N (f) HP P/N 1250-1750

Analyzer warm-up time: 1 hour

Perform this test to determine the minimum R channel input power level at which phase lock can be accomplished.

1. Connect the equipment as shown in Figure 2-18.

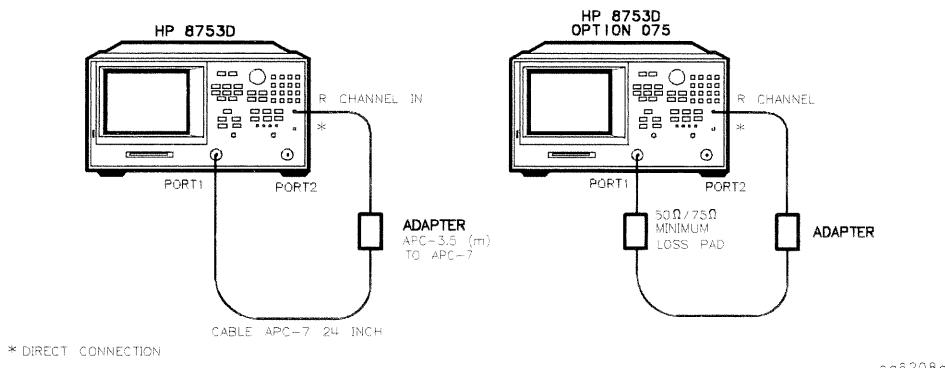


Figure 2-18. Minimum R Channel Level Test Setup

2-34 System Verification and Performance Tests

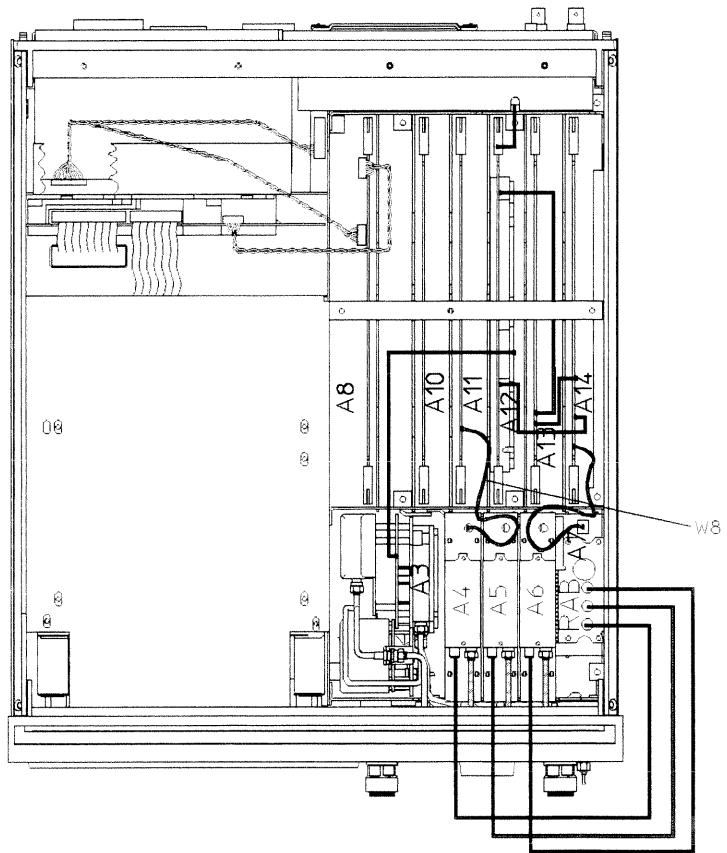
2. Press **[PRESET]** **[MEAS]** INPUT PORTS R.
3. Press **[MENU]** POWER PWR RANGE MAN POWER RANGES
RANGE 4 -55 to -30 .
4. Press **[SCALE REF]** REFERENCE VALUE **-70** **[x1]**.
5. Press **[MENU]** CW FREQ **300** **k/m**.
6. Press **[MENU]** POWER **-65** **[x1]**.
The analyzer displays the message CAUTION: NO IF FOUND: CHECK R INPUT LEVEL.
7. Press **[↑]** to increase the test port power by 1 dBm.
8. If the analyzer displays a phase lock error message, continue increasing the test port power until phase lock is achieved.
9. Write the test port power, that is displayed on the analyzer, on the "Performance Test Record."
10. Repeat steps 5 through 9 for the other CW frequencies listed in the "Performance Test Record."

In Case of Difficulty

1. Check the flexible RF cable (W8, as shown in Figure 2-19) between the R sampler assembly (A4) and the A11 phase lock assembly. Make sure it is connected between A11J1 (PL IF IN) and 1st IF Out.

Caution Loop the W8 cable around the A5 sampler as shown in Figure 2-19. *Do not* push the cable down next to the A11 phase lock assembly.

2-36 System Verification and Performance Tests



sg6209d

Figure 2-19. Flexible RF Cable Location

2. Using an ohmmeter, verify that the RF cable is not open. In addition, examine both the cable connectors - measure the resistance between the cable center pin and the cable connector and make sure it is *not* close to zero.
3. Check the R sampler by substituting it with the B sampler (A6).
 - a. Move cable W8 to the B sampler (A6), as shown in Figure 2-20.

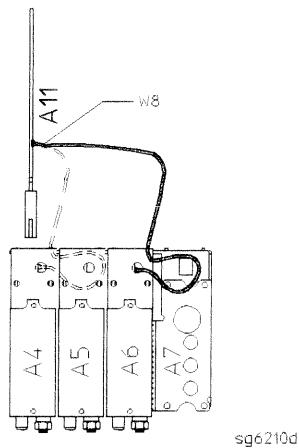


Figure 2-20. Connections for Substituting the R Sampler (A4)

4. Connect the equipment as shown in Figure 2-21.

2-38 System Verification and Performance Tests

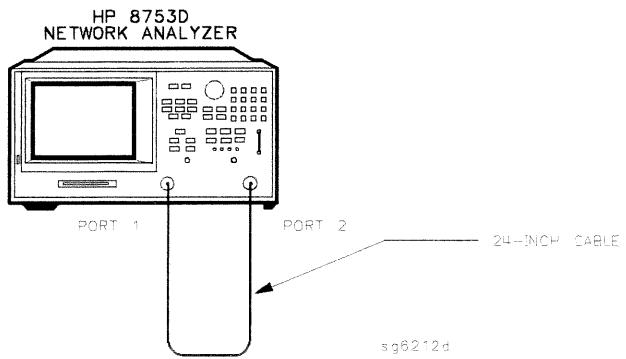


Figure 2-21. Setup for Checking the R Sampler (A4)

5. Repeat the test, but select the B sampler (A6) by pressing **[MEAS]** INPUT PORTS B in step 2. Use the following specifications:

300 kHz to 3 GHz <-27 dBm
3 GHz to 6 GHz <-22 dBm
6. If the analyzer fails the test, replace the A11 assembly.
7. Verify that the high/low band adjustments are still within specifications.
For more information on how to perform this task, refer to the "High/Low Band Transition Adjustment" located in the "Adjustments and Correction Constants" chapter.
8. Refer to the "Source Troubleshooting" chapter for more troubleshooting information.

6. Test Port Input Noise Floor Level

Specifications

Frequency Range	Test Port	IF Bandwidth	Average Noise Level
300 kHz to 3.0 GHz	Port 1	3 kHz	-82 dBm
300 kHz to 3.0 GHz	Port 1	10 Hz	-102 dBm
300 kHz to 3.0 GHz	Port 2	3 kHz	-82 dBm
300 kHz to 3.0 GHz	Port 2	10 Hz	-102 dBm
3.0 GHz to 6.0 GHz ¹	Port 1	3 kHz	-77 dBm
3.0 GHz to 6.0 GHz ¹	Port 1	10 Hz	-97 dBm
3.0 GHz to 6.0 GHz ¹	Port 2	3 kHz	-77 dBm
3.0 GHz to 6.0 GHz ¹	Port 2	10 Hz	-97 dBm

¹ Only for analyzer with Option 006.

Equipment Required for 50Ω Analyzers

Calibration Kit, 7 mm HP 85031B

Equipment Required for 75Ω Analyzers

Calibration Kit, Type-N HP 85036B

Analyzer warm-up time: 1 hour

Perform this test to determine the HP 8753D port 1 and port 2 noise floor levels at the input test ports.

Port 1 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 3 kHz)

1. Connect the equipment as shown in Figure 2-22.

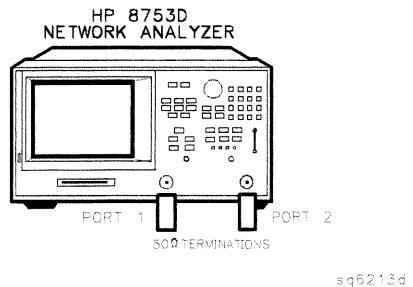


Figure 2-22. Source Input Noise Floor Test Setup

2. Press [PRESET] [MENU] POWER [-85] [x1] [STOP] [3] [G/n].
3. Press [MEAS] INPUT PORTS A TESTPORT 2 [FORMAT] LIN MAG [SCALE REF] AUTO SCALE .
4. Press [MARKER FCTN] MARKER MODE MENU STATS ON [MENU] TRIGGER MENU SINGLE .
5. When the analyzer finishes the sweep, notice the mean value (which appears on the analyzer display).
6. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

Note

Notice that the mean value that is displayed on the analyzer is in μ Units. So, for example, if the displayed value is 62 μ U, the value that you would put in the equation is (62×10^{-6}) .

7. Write this calculated value on the "Performance Test Record."

Port 1 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 10 Hz)

8. Press **AVG** IF BW **10** **x1** to change the IF bandwidth to 10 Hz.
9. Press **MENU** TRIGGER MENU SINGLE.
10. When the analyzer finishes the sweep, notice the mean value.
11. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

12. Write this calculated value on the “Performance Test Record.”

Port 2 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 10 Hz)

13. Press **MEAS** INPUT PORTS B TESTPORT 1 **FORMAT** LIN MAG.
14. Press **MENU** TRIGGER MENU SINGLE.
15. When the analyzer finishes the sweep, notice the mean value.
16. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

17. Write this calculated value on the “Performance Test Record.”

Port 2 Noise Floor Level from 300 kHz to 3 GHz (IF BW = 3 kHz)

18. Press **AVG** **IF BW** **③** **k/m** to change the IF bandwidth to 3 kHz.
19. Press **MENU** **TRIGGER MENU SINGLE**.
20. When the analyzer finishes the sweep, notice the mean value.
21. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

22. Write this calculated value on the “Performance Test Record.”
23. This completes the “Test Port Input Noise Floor Level” procedure if your analyzer does not have Option 006. Otherwise continue with the next section.

Port 2 Noise Floor Level from 3 GHz to 6 GHz (IF BW = 3 kHz)

24. Press **START** **③** **G/n** **STOP** **⑥** **G/n**.
25. Press **MENU** **TRIGGER MENU SINGLE**.
26. When the analyzer finishes the sweep, notice the mean value.
27. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

28. Write this calculated value on the “Performance Test Record.”

Port 2 Noise Floor Level from 3 GHz to 6 GHz (IF BW = 10 Hz)

29. Press **AVG** IF BW **[10]** **[x1]** to change the IF bandwidth to 10 Hz.
30. Press **MENU** TRIGGER MENU SINGLE.
31. When the analyzer finishes the sweep, notice the mean value.
32. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

33. Write this calculated value on the “Performance Test Record.”

Port 1 Noise Floor Level for 3 GHz to 6 GHz (IF BW = 10 Hz)

34. Press **MEAS** INPUT PORTS A TESTPORT 2.
35. Press **MENU** TRIGGER MENU SINGLE.
36. When the analyzer finishes the sweep, notice the mean value.
37. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

38. Write this calculated value on the “Performance Test Record.”

Port 1 Noise Floor Level from 3 GHz to 6 GHz (IF BW = 3 kHz)

39. Press **AVG** IF BW **[3]** **[k/m]**.
40. Press **MENU** TRIGGER MENU SINGLE.
41. When the analyzer finishes the sweep, notice the mean value.
42. Convert the measured linear magnitude mean value to log magnitude, using this equation.

$$\text{Power (dBm)} = 20 * [\log_{10}(\text{linear magnitude mean value})]$$

43. Write this calculated value on the “Performance Test Record.”

2-44 System Verification and Performance Tests

In Case of Difficulty

1. Perform the “ADC Linearity Correction Constants (Test 52),” located in the “Adjustments and Correction Constants” chapter.
2. Repeat the “Test Port Input Noise Floor Level” procedure.
3. Suspect the A10 Digital IF assembly if the analyzer fails both test port input noise floor tests.
4. Refer to the “Receiver Troubleshooting” chapter for more troubleshooting information.

7. Test Port Input Frequency Response

Specifications

Frequency Range	Test Port	Input Frequency Response
300 kHz to 3 GHz	Port 1	±1 dB
300 kHz to 3 GHz	Port 2	±1 dB
3 GHz to 6 GHz ¹	Port 1	±2 dB
3 GHz to 6 GHz ¹	Port 2	±2 dB

¹ Only for analyzers with Option 006.

Equipment Required for 50Ω Analyzers

Power Meter HP 436A/437B/438A
Power Sensor HP 8482A
Cable, APC-7 24-inch HP P/N 8120-4779
Adapter, APC-7 to Type-N (f) HP 11524A

Additional Equipment Required for Analyzers with Option 006

Power Sensor HP 8481A

Equipment Required for 75Ω Analyzers

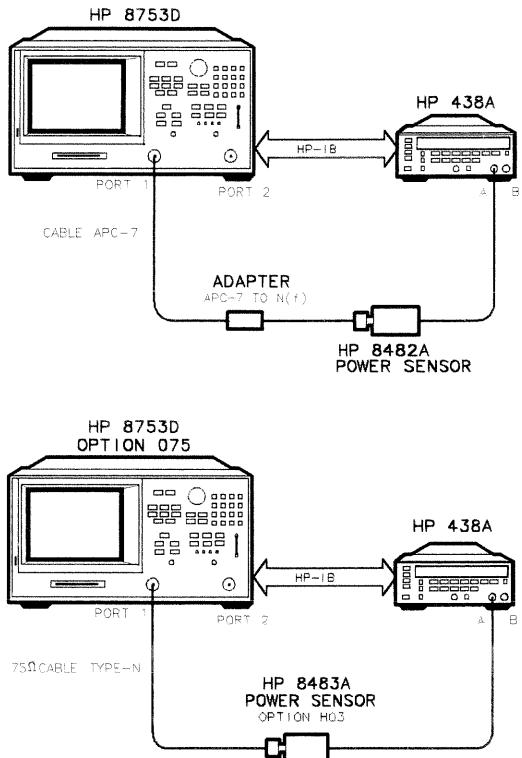
Power Meter HP 436A/437B/438A
Power Sensor HP 8483A Option H03
Cable, Type-N HP P/N 8120-2408

Analyzer warm-up time: 1 hour

Perform this test to examine the vector sum of all test setup error vectors in both magnitude and phase change as a function of frequency.

Power Meter Calibration for Test Port 1 from 300 kHz to 3 GHz

1. Zero and calibrate the power meter.
2. Connect the equipment as shown in Figure 2-23.



sg6214d

Figure 2-23. Setup for Power Meter Calibration on Test Port 1

3. Press [PRESET] [START] [300] [k/m].
4. **Only for Analyzers with Option 006:** Press [STOP] [3] [G/n].
5. Press [LOCAL] SYSTEM CONTROLLER.
6. Press SET ADDRESSES and POWER MTR until the analyzer shows the correct power meter model.

7. Press ADDRESS: P MTR/HPIB . The default power meter HP-IB address is 13. Make sure it is the same as your power meter HP-IB address. Otherwise, use the analyzer front panel keypad to enter the correct HP-IB address for your power meter.
8. Press **MENU** NUMBER of POINTS **51** **x1**.
9. Press POWER PWR RANGE MAN to turn the auto power range off.

Note The analyzer displays the PR_m annotation, indicating that the analyzer power range is set to MANUAL.

10. Press PORT POWER to uncouple the test port output power.
11. Press **CAL** PWRMTR CAL .
12. Press LOSS/SENSR LISTS CAL FACTOR SENSOR A . Refer to the back of the power sensor to locate the different calibration factor values along with their corresponding frequencies.

Note The analyzer's calibration factor sensor table can hold a MAXIMUM of 12 calibration factor data points.

The following softkeys are included in the sensor calibration factor entries menu:

SEGMENT	press to select a point where you can use the front panel knob or entry keys to enter a value
EDIT	press to edit or change a previously entered value
DELETE	press to delete a point from the sensor calibration factor table
ADD	select this key to add a point into the sensor calibration factor table
CLEAR LIST	select this key to erase the entire sensor calibration factor table
DONE	select this key when done entering points to the sensor calibration factor table

2-48 System Verification and Performance Tests

As an example, the following are the keystrokes for entering the first two calibration factor data points for the HP 8482A power sensor (assuming CF% = 96.4 at 100 kHz and CF% = 98.4 at 300 kHz):

- a. From the sensor calibration factor entries menu, press ADD .
- b. Press FREQUENCY **[100] [k/m]**. If you make an entry error, press **[]** and re-enter the correct value again.
- c. Press CAL FACTOR **[96.4] [x1]**.
- d. Press DONE to terminate the first calibration factor data point entry.
- e. To enter the second cal factor data point, press ADD .
- f. Press FREQUENCY **[300] [k/m]**.
- g. Press CAL FACTOR **[98.4] [x1]**.
- h. To terminate the second calibration factor data point entry, press DONE .
- i. Press SEGMENT and use the front panel knob to scroll through the sensor calibration factors table. Check to be sure all values are entered correctly. If you spot an error, use the front panel knob to point to the data point you want to modify and press EDIT .
13. Press the appropriate softkeys to create a power sensor calibration factors table.
14. Press DONE to exit the sensor calibration factor entries menu.
15. Press RETURN ONE SWEEP TAKE CAL SWEEP to start the power meter calibration.

Wait until the analyzer finishes the sweep, then continue with this procedure.

Note	The analyzer displays the PC annotation, indicating the power meter calibration is done and the error correction is active.
-------------	---

Test Port 2 Input Frequency Response from 300 kHz to 3GHz

16. Connect the equipment as shown in Figure 2-24.

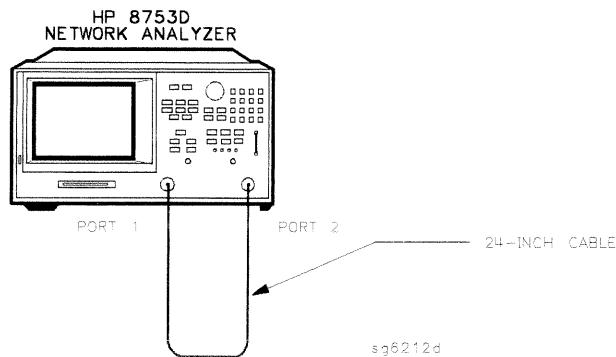


Figure 2-24. Test Port 2 Input Frequency Response Test Setup

17. Press **MEAS INPUT PORTS B**.
18. Press **SCALE REF SCALE/DIV (1) (x1)**.
19. Press **MARKER MARKER 1 MARKER FCTN MKR SEARCH SEARCH:MIN** to put marker 1 at the minimum magnitude location of the trace.
20. Press **MARKER MARKER 2 MARKER FCTN MKR SEARCH SEARCH:MAX** to position marker 2 at the maximum magnitude location of the trace.
21. Write the marker 1 or marker 2 value (which appears on the analyzer display), whichever has the larger absolute magnitude, in the "Performance Test Record."

2-50 System Verification and Performance Tests

Power Meter Calibration on Port 2 from 300 kHz to 3 GHz

22. Connect the equipment as shown Figure 2-25.

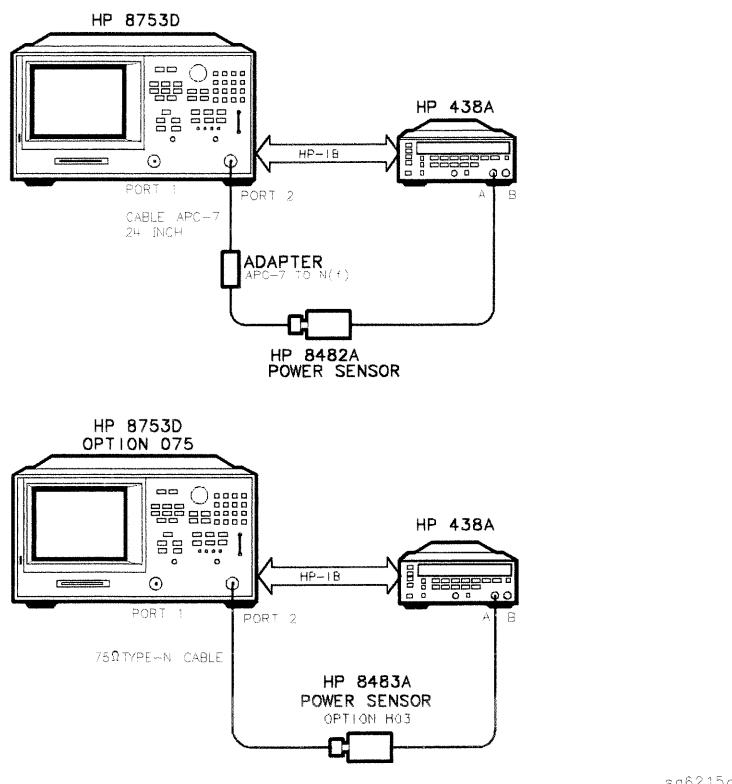


Figure 2-25. Setup for Power Meter Calibration on Test Port 2

23. Press **[MEAS] INPUT PORTS TESTPORT 2**.
24. Press **[CAL] PWRMTR CAL ONE SWEEP TAKE CAL SWEEP** to start the power meter calibration for test port 2.
25. When the analyzer displays the message POWER METER CALIBRATION SWEEP DONE, connect the equipment as shown as in Figure 2-26.

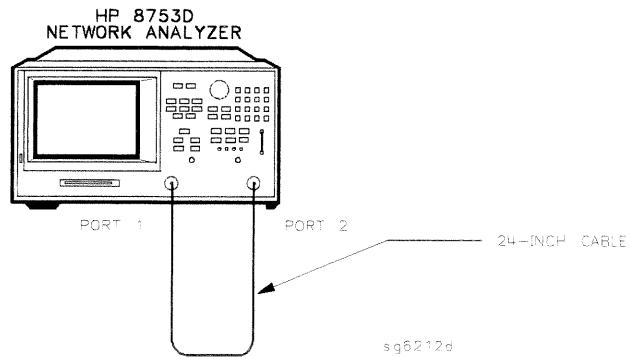


Figure 2-26. Test Port 1 Input Frequency Response Test Setup

Test Port 1 Input Frequency Response from 300 kHz to 3 GHz

26. Press [MEAS] INPUT PORTS A.
27. Press [MARKER] MARKER 1 [MARKER FCTN] MKR SEARCH SEARCH:MIN.
28. Press [MARKER] MARKER 2 [MARKER FCTN] MKR SEARCH SEARCH:MAX.
29. Write the marker 1 or marker 2 reading, whichever has the larger absolute magnitude, in the "Performance Test Record."
30. This completes the "Test Port Input Frequency Response" procedure if your analyzer does not have Option 006. Otherwise continue with the next sections.

Power Meter Calibration for Test Port 2 from 3 GHz to 6 GHz

31. Replace the power sensor with the HP 8481A, and then setup the power meter:
 - If the power meter is an HP 438A, press [LCL].
 - If the power meter is an HP 437B, press [PRESET/LOCAL].
 - If the power meter is an HP 436A, cycle the line power.
32. Connect the equipment as shown in Figure 2-27.

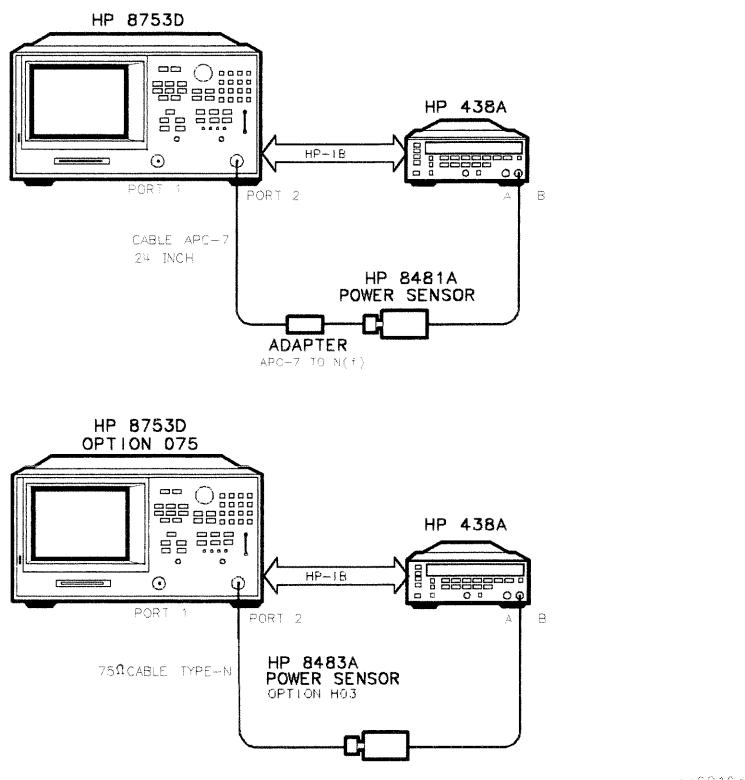


Figure 2-27. Setup for Power Meter Calibration on Test Port 2

33. Press **START** 3 **G/n** **STOP** 6 **G/n**.
34. Press **CAL** **PWRMTR CAL**.
35. Press **LOSS/SENSR LISTS** **CAL FACTOR SENSOR B**. Repeat step 10 to build a calibration factor sensor table for the HP 8481A power sensor.
36. Press **DONE** to exit the sensor calibration factor entries menu.
37. To select the HP 8481A power sensor, press **USE SENSOR B**.
38. Press **RETURN** **TAKE CAL SWEEP** to start the power meter calibration.

Test Port 1 Input Frequency Response from 3 GHz to 6 GHz

39. When the analyzer finishes the calibration sweep, connect the equipment as shown in Figure 2-28.

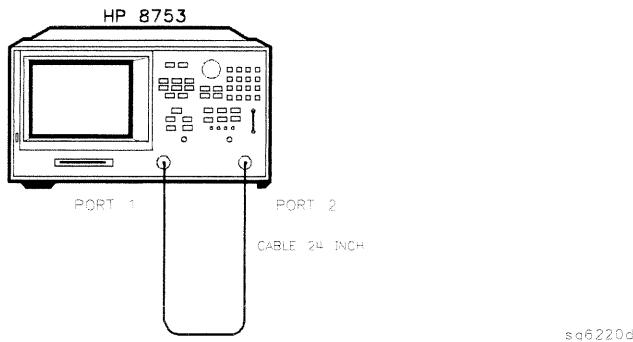


Figure 2-28. Setup for Test Port 1 Input Frequency Response

40. Press [MEAS] INPUT PORTS A.
41. Press [MARKER] MARKER 1 [MARKER FCTN] MKR SEARCH SEARCH:MIN to put marker 1 at the minimum magnitude location of the trace.
42. Press [MARKER] MARKER 2 [MARKER FCTN] MKR SEARCH SEARCH:MAX to position marker 2 at the maximum magnitude location of the trace.
43. Write the marker 1 or marker 2 reading, whichever has the largest absolute magnitude, in the "Performance Test Record."

Power Meter Calibration on Test Port 1 from 3 GHz to 6 GHz

44. Connect the equipment as shown in Figure 2-29.

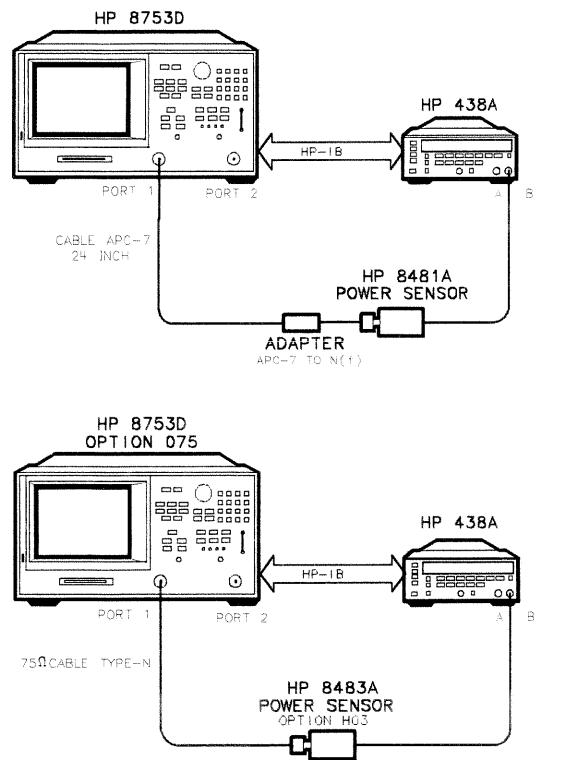


Figure 2-29. Setup for Power Meter Calibration on Test Port 1

45. Press **[MEAS] INPUT PORTS TESTPORT 1**.
46. Press **[CAL] PWRMTR ONE SWEEP TAKE CAL SWEEP** to start the power meter calibration for output test port 1.

Test Port 2 Input Frequency Response from 3 GHz to 6 GHz

47. When the analyzer displays the message POWER METER CALIBRATION SWEEP DONE, connect the equipment as shown as in Figure 2-30.

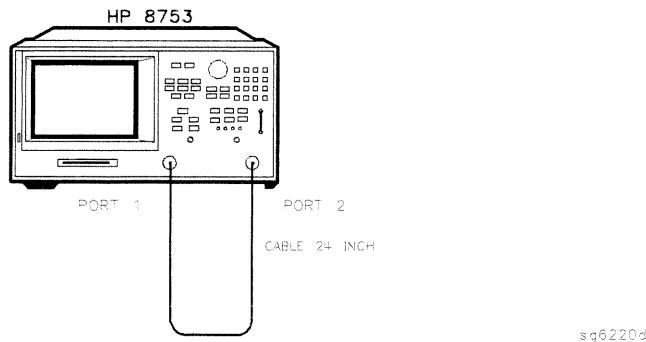


Figure 2-30. Test Port 2 Input Frequency Response Test Setup

48. Press [MEAS] INPUT PORTS B.
49. Press [MARKER] MARKER 1 [MARKER FCTN] MKR SEARCH SEARCH:MIN.
50. Press [MARKER] MARKER 2 [MARKER FCTN] MKR SEARCH SEARCH:MAX.
51. Write the marker 1 or marker 2 reading, whichever has the largest magnitude, in the "Performance Test Record."

In Case of Difficulty

1. Be sure you have used the correct power sensor for the frequency range.
2. Verify that the calibration factors that you have entered for the power sensors are correct.
3. Repeat this test with a "known good" thru cable.

8. Test Port Crosstalk

Specifications

Frequency Range	Crosstalk ¹
300 kHz to 3 GHz	100 dB
3 GHz to 6 GHz ²	90 dB

1 At 25 °C ±5 °C.

2 Only for analyzers with Option 006.

Required Equipment for 50Ω Analyzers

Calibration Kit, 7 mm HP 85031B
Cable, APC-7 24-inch HP P/N 8120-4779

Required Equipment for 75Ω Analyzers

Calibration Kit, 75Ω, Type-N HP 85036B

Analyzer warm-up time: 1 hour

Perform this test to verify the signal leakage between the analyzer's test ports.

1. Connect the equipment as shown in Figure 2-31.

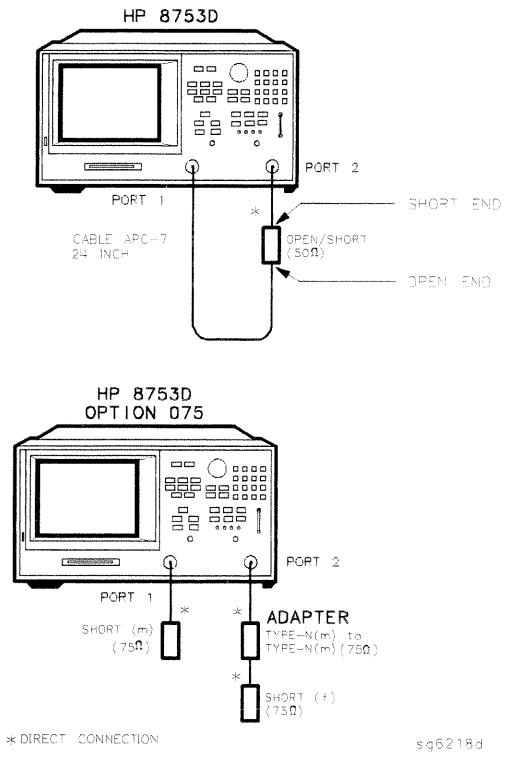


Figure 2-31. Test Port Crosstalk Test Setup

2. Press [PRESET] [MENU] POWER [10] [x1].
3. Press [AVG] IF BW [10] [x1].

2-58 System Verification and Performance Tests

Crosstalk to Test Port 2 from 300 kHz to 3 GHz

4. Press [START] 300 [k/m] [STOP] 3 [G/n].
5. Press [MEAS] Trans: FWD S21 (B/R) .
6. Press [SCALE REF] REFERENCE VALUE [-100] [$\times 1$].
7. Press [MENU] TRIGGER MENU SINGLE .
8. Press [MARKER FCTN] MKR SEARCH SEARCH: MAX .
9. Write the marker value (which appears on the analyzer display) in the "Performance Test Record."

Crosstalk to Test Port 1 from 300 kHz to 3 GHz

10. Press [MEAS] Trans: REV S12 (A/R) .
11. Press [MENU] TRIGGER MENU SINGLE .
12. Press [MARKER FCTN] MKR SEARCH SEARCH: MAX .
13. Write the marker value (which appears on the analyzer display) in the "Performance Test Record."
14. This completes the "Test Port Crosstalk" performance test if your analyzer does not have Option 006. Otherwise, proceed to the next section.

Crosstalk to Test Port 1 from 3 GHz to 6 GHz

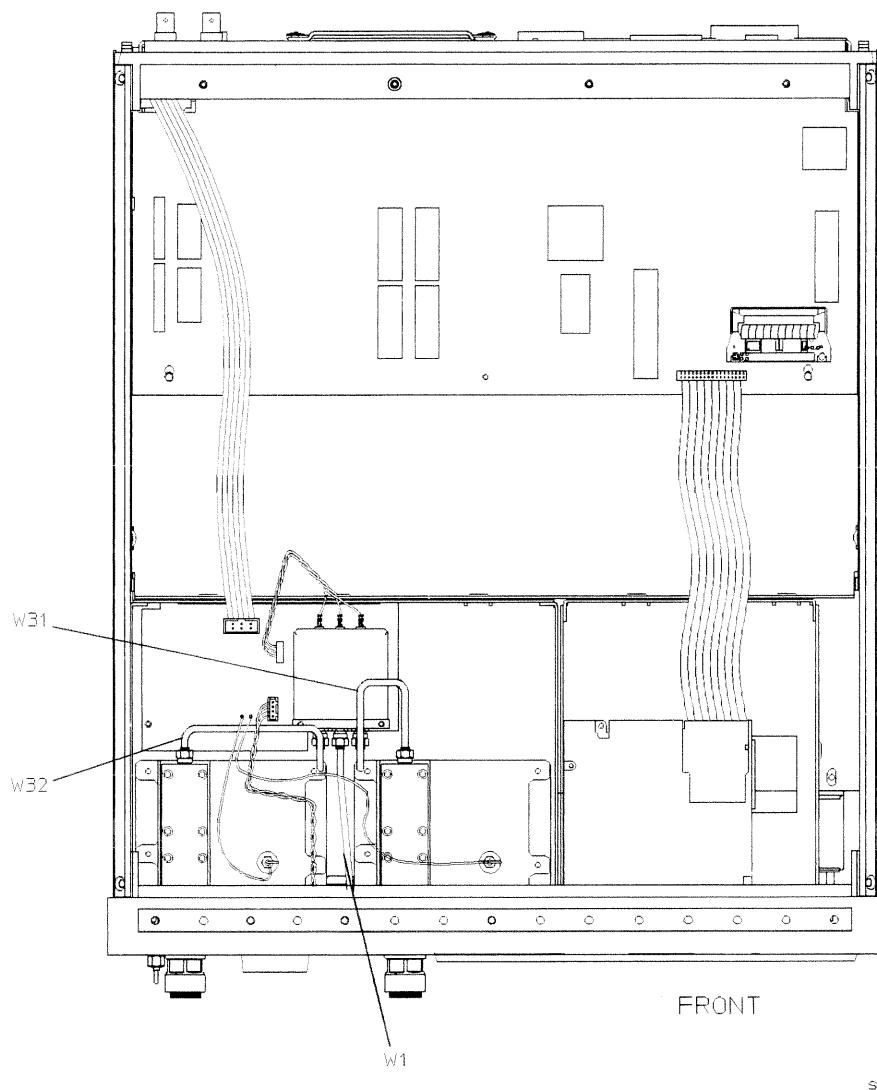
15. Press [START] 3 [G/n] [STOP] 6 [G/n].
16. Press [MENU] TRIGGER MENU SINGLE .
17. Press [MARKER FCTN] MKR SEARCH SEARCH: MAX .
18. Write the marker value (which appears on the analyzer display) in the "Performance Test Record."

Crosstalk to Test Port 2 from 3 GHz to 6 GHz

1. Press [MEAS] Trans: FWD S21 (B/R).
2. Press [MENU] TRIGGER MENU SINGLE.
3. Press [MARKER FCTN] MKR SEARCH SEARCH: MAX.
4. Write the marker value (which appears on the analyzer display) in the "Performance Test Record."

In Case of Difficulty

1. Remove the instrument top cover. Using an 8 lb-inch torque wrench, verify that ALL semi-rigid cables connected to the sampler/mixer assemblies are tight. In addition tighten any loose screws on the sampler/mixer assemblies (A4/5/6) and the pulse generator assembly (A7).
2. Remove the instrument bottom cover. Refer to Figure 2-32. Verify that cables W1, W31 and W32 are tight.
3. Repeat this test.



sg6211d

Figure 2-32. HP 8753D Bottom View

9. Calibration Coefficients

Specifications

Uncorrected ¹ Error Terms	Frequency Range		
	300 kHz to 1.3 GHz	1.3 GHz to 3 GHz	3 GHz to 6 GHz ²
Directivity	35 dB	30 dB	25 dB
Source Match	16 dB	16 dB	14 dB
Load Match	18 dB	16 dB	14 dB
Transmission Tracking	±1.5 dB	±1.5 dB	±2.5 dB
Reflection Tracking	±1.5 dB	±1.5 dB	±2.5 dB

1 At 25 °C ±5 °C, with less than 1 °C deviation from the measurement calibration temperature.

2 Only for analyzers with Option 006.

Equipment Required for 50Ω Analyzers

Calibration Kit, 7 mm HP 85031B
Cable, APC-7, 24-inch HP P/N 8120-4779

Equipment Required for 75Ω Analyzers

Calibration Kit, Type-N HP 85036B
Cable, Type-N, 24-inch HP P/N 8120-4781

Analyzer warm-up time: 30 minutes

Perform this procedure to verify the analyzer uncorrected test port characteristics.

Note The crosstalk calibration coefficients are omitted in this procedure. They are covered in the "Test Port Crosstalk" performance test.

First Full 2-Port Calibration

1. Connect the equipment as shown in Figure 2-33.

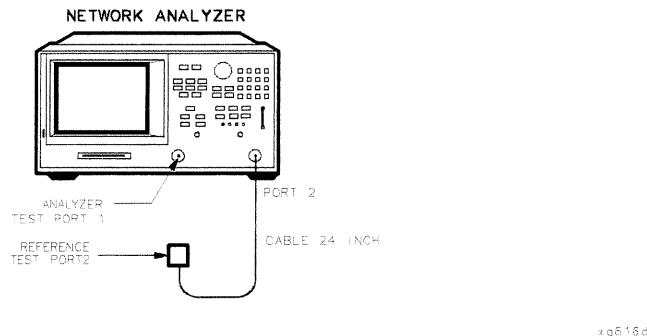


Figure 2-33. First Full 2-Port Calibration Test Setup

2. Press [PRESET] [START] [300] [k/m].
3. Press [CAL] CAL KIT SELECT CAL KIT CAL KIT:7mm RETURN RETURN
CALIBRATE MENU FULL 2-PORT .
4. Press ISOLATION OMIT ISOLATION .
5. Connect the "open" end of the open/short combination (supplied in the calibration kit) to analyzer test port 1.
6. Press REFLECTION FORWARD:OPEN .
7. Connect the "short" end of the open/short combination to analyzer test port 1.
8. Press FORWARD:SHORT .
9. Replace the open/short combination with the 50 ohm termination (supplied in the calibration kit).
10. Press FORWARD:LOAD .
11. Connect the "open" end of the open/short combination to the reference test port 2.

12. Press REVERSE:OPEN .
13. Connect the "short" end of the open/short combination to the reference test port 2.
14. Press REVERSE: SHORT .
15. Connect the 50 ohm termination to the reference test port 2.
16. Press REVERSE: LOAD .
17. At the prompt, PRESS 'DONE' IF FINISHED WITH STD(s), press STANDARDS DONE .
Wait for the message COMPUTING CAL COEFFICIENTS to disappear from the analyzer display before proceeding to the next step.
18. Connect the equipment as shown in Figure 2-34.

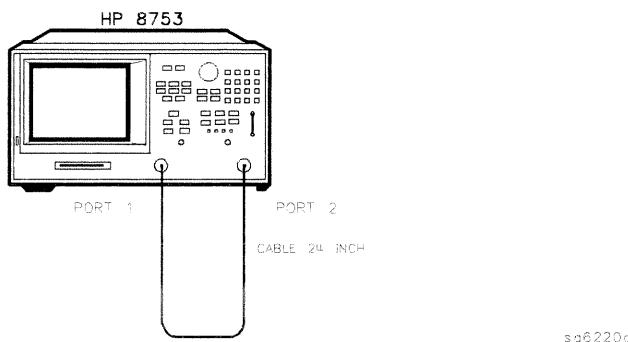


Figure 2-34. Transmission Calibration Test Setup

19. Press TRANSMISSION DO BOTH FWD + REV .
20. Press DONE 2-PORT CAL .

2-64 System Verification and Performance Tests

Directivity (Forward) Calibration Coefficient

21. Press **SYSTEM** SERVICE MENU TESTS **(32)** **(x1)** EXECUTE TEST.
22. When the analyzer finishes the test, press **MARKER**.
23. Using the front panel knob, locate the maximum value of the data trace for the 300 kHz to 1.3 GHz frequency range.
24. Write the maximum value in the “Performance Test Record.”
25. Repeat the previous two steps for the other frequency range(s) listed on the “Performance Test Record.”

Source Match (Forward) Calibration Coefficient

26. Press **SYSTEM** SERVICE MENU TESTS **(33)** **(x1)** EXECUTE TEST.
27. When the analyzer finishes the test, repeat steps 22 through 25.

Transmission Tracking (Forward) Calibration Coefficient

28. Press **SYSTEM** SERVICE MENU TESTS **(37)** **(x1)** EXECUTE TEST.
29. When the analyzer finishes the test, repeat steps 22 through 25.

Reflection Tracking (Forward) Calibration Coefficient

30. Press **SYSTEM** SERVICE MENU TESTS **(34)** **(x1)** EXECUTE TEST.
31. When the analyzer finishes the test, repeat steps 22 through 25.

Load Match (Reverse) Calibration Coefficient

32. Press **SYSTEM** SERVICE MENU TESTS **(42)** **(x1)** EXECUTE TEST.
33. When the analyzer finishes the test, repeat steps 22 through 25.

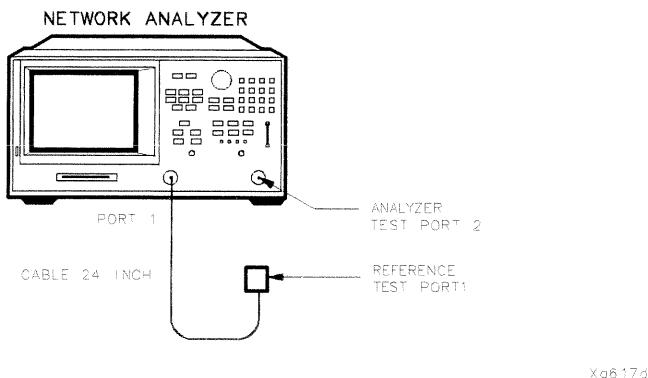
Transmission Tracking (Reverse) Calibration Coefficient

34. Press **SYSTEM SERVICE MENU TESTS** **43** **x1** **EXECUTE TEST**.

35. When the analyzer finishes the test, repeat steps 22 through 25.

Second Full 2-Port Calibration

36. Connect the equipment as shown in Figure 2-35.



Xg617d

Figure 2-35. Second Full 2-Port Calibration Test Setup

37. Press **PRESET** **START** **300** **k/m**.

38. Press **CAL** **CAL KIT** **SELECT CAL KIT** **CAL KIT:7mm** **RETURN** **RETURN** **CALIBRATE MENU** **FULL 2-PORT**.

39. Press **ISOLATION** **OMIT ISOLATION**.

40. Connect the "open" end of the open/short combination (supplied in the calibration kit) to reference test port 1.

41. Press **REFLECTION FORWARD:OPEN**.

42. Connect the "short" end of the open/short combination to reference test port 1.

43. Press **FORWARD:SHORT**.

2-66 System Verification and Performance Tests

44. Replace the open/short combination with the 50 ohm termination (supplied in the calibration kit).
45. Press FORWARD:LOAD .
46. Connect the “open” end of the open/short combination to the analyzer test port 2.
47. Press REVERSE:OPEN .
48. Connect the “short” end of the open/short combination to the analyzer test port 2.
49. Press REVERSE: SHORT .
50. Connect the 50 ohm termination to the analyzer test port 2.
51. Press REVERSE: LOAD .
52. When the analyzer displays PRESS ‘DONE’ IF FINISHED WITH STD(s), press STANDARDS DONE .
Wait for the message COMPUTING CAL COEFFICIENTS to disappear from the analyzer display before proceeding to the next step.
53. Connect the equipment as shown in Figure 2-36.

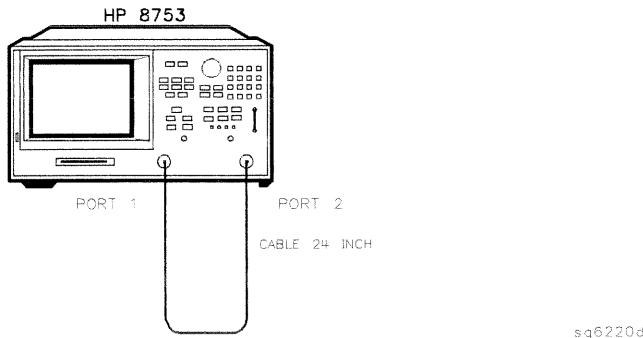


Figure 2-36. Transmission Calibration Test Setup

54. Press TRANSMISSION DO BOTH FWD + REV .

55. When the analyzer finishes the test, press ISOLATION DONE
DONE 2-PORT CAL .

Load Match (Forward) Calibration Coefficient

56. Press **SYSTEM** SERVICE MENU TESTS **(36)** **x1** EXECUTE TEST .
57. When the test is done, press **MARKER** MARKER 1.
58. Using the front panel knob, locate the maximum value of the data trace for the 300 kHz to 1.3 GHz frequency range.
59. Write the maximum value on the “Performance Test Record.”
60. Repeat the previous three steps for the other frequency range(s) listed on the “Performance Test Record.”

Directivity (Reverse) Calibration Coefficient

61. Press **SYSTEM** SERVICE MENU TESTS **(38)** **x1** EXECUTE TEST .
62. When the analyzer finishes the test, repeat steps 57 through 60.

Source Match (Reverse) Calibration Coefficient

63. Press **SYSTEM** SERVICE MENU TESTS **(39)** **x1**. At the prompt, press EXECUTE TEST .
64. When the analyzer finishes the test, repeat steps 57 through 60.

Reflection Tracking (Reverse) Calibration Coefficient

1. Press **SYSTEM** SERVICE MENU TESTS **(40)** **x1** EXECUTE TEST .
2. When the analyzer finishes the test, repeat steps 57 through 60.

10. System Trace Noise (Only for Analyzers without Option 006)

Frequency Range	Ratio	System Trace Noise (Magnitude ¹)	System Trace Noise (Phase ¹)
30 kHz to 3 GHz	A/R	<0.006 dB rms	<0.038° rms
30 kHz to 3 GHz	B/R	<0.006 dB rms	<0.038° rms

1 At +5 dBm into test port, 3 kHz IF bandwidth, and CW sweep.

Required Equipment for 50Ω Analyzers

Cable, APC-7, 24-inch HP P/N 8120-4779

Required Equipment for 75Ω Analyzers

Cable, 75Ω, Type-N 24-inch HP P/N 8120-2408

Analyzer warm-up time: 1 hour

Perform this test to measure the system trace noise at a designated frequency in both the A/R and B/R ratioed measurements.

1. Connect the equipment as shown in Figure 2-37.

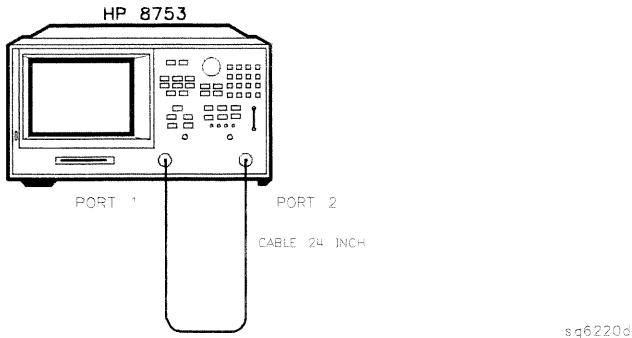


Figure 2-37. System Trace Noise Test Setup

2. Press [PRESET] [MENU] POWER [5] [x1].

3. Press RETURN CW FREQ **(3)** **G/n** NUMBER of POINTS **(1601)** **(x1)**.
4. Press **[MARKER FCTN]** MARKER MODE MENU STATS ON to activate the instrument's statistic feature.

System Trace Noise for A/R Magnitude

5. Press **[MEAS]** Trans: REV S12 (A/R).
6. Press **[MENU]** TRIGGER MENU NUMBER of GROUPS **(5)** **(x1)**.
7. When the analyzer displays the "Hld" annotation, press **[SCALE REF]** AUTO SCALE .
8. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the "Performance Test Record."

System Trace Noise for A/R Phase

9. Press **[FORMAT]** PHASE .
10. Press **[MENU]** TRIGGER MENU NUMBER of GROUPS **(5)** **(x1)**.
11. When the analyzer finishes the number of sweeps, press **[SCALE REF]** AUTO SCALE .
12. Write the s.dev (standard deviation) value on the "Performance Test Record."

System Trace Noise for B/R Magnitude

13. Press **[MEAS]** Trans: FWD S21 (B/R) .
14. Press **[MENU]** TRIGGER MENU NUMBER of GROUPS **(5)** **(x1)**.
15. When the analyzer finishes the number of sweeps, press **[SCALE REF]** AUTO SCALE .
16. Write the s.dev (standard deviation) value on the "Performance Test Record."

2-70 System Verification and Performance Tests

System Trace Noise for B/R Phase

17. Press **[FORMAT]** **PHASE**.
18. Press **[MENU]** **TRIGGER MENU** **NUMBER of GROUPS** **5** **[x1]**.
19. When the analyzer finishes the number of sweeps, press **[SCALE REF]** **AUTO SCALE**.
20. Write the s.dev (standard deviation) value on the “Performance Test Record.”

In Case of Difficulty

1. Perform the “ADC Offset Correction Constants” procedure, located in the “Adjustments and Correction Constants” chapter.
2. Repeat this performance test.
3. Suspect the A10 Digital IF board assembly if the analyzer still fails the test.

11. System Trace Noise (Only for Analyzers with Option 006)

Specifications

Frequency Range	Ratio	System Trace Noise (Magnitude ¹)	System Trace Noise (Phase ¹)
30 kHz to 3 GHz	A/R	<0.006 dB rms	<0.038° rms
30 kHz to 3 GHz	B/R	<0.006 dB rms	<0.038° rms
3 GHz to 6 GHz	A/R	<0.010 dB rms	<0.070° rms
3 GHz to 6 GHz	B/R	<0.010 dB rms	<0.070° rms

¹ At +5 dBm into test port, 3 kHz IF bandwidth, and CW sweep.

Required Equipment

Cable, APC-7, 24-inch HP P/N 8120-4779

Analyzer warm-up time: 1 hour

Perform this test to measure the system trace noise at designated CW frequencies in both the A/R and B/R ratioed measurements.

1. Connect the equipment as shown in Figure 2-38.

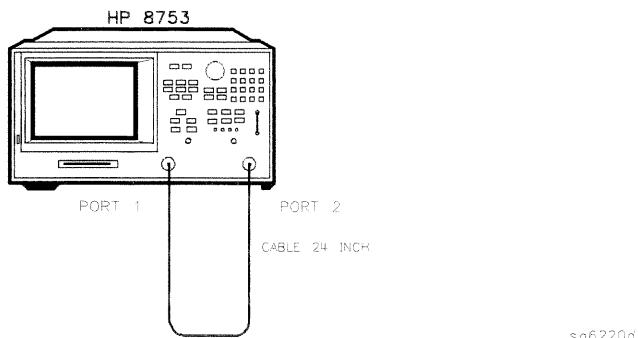


Figure 2-38. System Trace Noise Test Setup

2-72 System Verification and Performance Tests

2. Press [PRESET] [MENU] POWER [5] [x1] RETURN NUMBER of POINTS [1601] [x1].
3. Press [MARKER FCTN] MARKER MODE MENU STATS ON to activate the instrument's statistic feature.

System Trace Noise for A/R Magnitude from 30 kHz to 3 GHz

4. Press [MEAS] Trans: REV S12 (A/R).
5. Press [MENU] CW FREQ [3] [G/n] TRIGGER MENU NUMBER of GROUPS [5] [x1].
6. When the analyzer finishes the number of sweeps, press [SCALE REF] AUTO SCALE .
7. Write the s.dev (standard deviation) value shown, which appears on the analyzer display, on the "Performance Test Record."

System Trace Noise for A/R Magnitude from 3 GHz to 6 GHz

8. Press [MENU] CW FREQ [6] [G/n] TRIGGER MENU NUMBER of GROUPS [5] [x1].
9. When the analyzer finishes the number of sweeps, press [SCALE REF] AUTO SCALE .
10. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the "Performance Test Record."

System Trace Noise for A/R Phase from 3 GHz to 6 GHz

11. Press [FORMAT] PHASE .
12. Press [MENU] TRIGGER MENU NUMBER of GROUPS [5] [x1].
13. When the analyzer finishes the number of sweeps, press [SCALE REF] AUTO SCALE .
14. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the "Performance Test Record."

System Trace Noise for A/R Phase from 30 kHz to 3 GHz

15. Press **MENU** CW FREQ **3** **G/n** TRIGGER MENU NUMBER of GROUPS **5** **x1**.
16. When the analyzer finishes the number of sweeps, press **SCALE REF** **AUTO SCALE**.
17. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the “Performance Test Record.”

System Trace Noise for B/R Magnitude from 30 kHz to 3 GHz

18. Press **MEAS** Trans: FWD S21 (B/R) **MENU** TRIGGER MENU NUMBER of GROUPS **5** **x1**.
19. When the analyzer finishes the number of sweeps, press **SCALE REF** **AUTO SCALE**.
20. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the “Performance Test Record.”

System Trace Noise for B/R Magnitude from 3 GHz to 6 GHz

21. Press **MENU** CW FREQ **6** **G/n** TRIGGER MENU NUMBER of GROUPS **5** **x1**.
22. When the analyzer finishes the number of sweeps, press **SCALE REF** **AUTO SCALE**.
23. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the “Performance Test Record.”

System Trace Noise for B/R Phase from 3 GHz to 6 GHz

24. Press **FORMAT** PHASE **MENU** TRIGGER MENU NUMBER of GROUPS **5** **x1**.
25. When the analyzer finishes the number of sweeps, press **SCALE REF** **AUTO SCALE**.
26. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the “Performance Test Record.”

2.74 System Verification and Performance Tests

System Trace Noise for B/R Phase from 30 kHz to 3 GHz

27. Press **MENU** CW FREQ **③** **G/n** TRIGGER MENU NUMBER of GROUPS **⑤** **x1**.
28. When the analyzer finishes the number of sweeps, press **SCALE REF**
AUTO SCALE.
29. Write the s.dev (standard deviation) value, which appears on the analyzer display, on the “Performance Test Record.”

In Case of Difficulty

1. Perform the “ADC Offset Correction Constants” procedure, located in the “Adjustments and Correction Constants” chapter.
2. Repeat this performance test.
3. Suspect the A10 Digital IF board assembly if the analyzer still fails the test.

12. Test Port Input Impedance

Specifications

Frequency Range	Test Port Input	Return Loss
30 kHz to 300 kHz ¹	Port 1	≥ 14 dB
50 kHz to 300 kHz ²	Port 1	≥ 20 dB
300 kHz to 1.3 GHz	Port 1	≥ 18 dB
1.3 GHz to 3 GHz	Port 1	≥ 16 dB
3 GHz to 6 GHz ³	Port 1	≥ 14 dB
30 kHz to 300 kHz ¹	Port 1	≥ 14 dB
50 kHz to 300 kHz ²	Port 2	≥ 20 dB
300 kHz to 1.3 GHz	Port 2	≥ 18 dB
1.3 GHz to 3 GHz	Port 2	≥ 16 dB
3 GHz to 6 GHz ³	Port 2	≥ 14 dB

1 Typical for analyzers with Option 075.

2 Only for analyzers without Option 006 — 30 kHz to 3 GHz range.

3 Only for analyzers with Option 006 — 30 kHz to 6 GHz range.

Required Equipment for 50Ω Analyzers

Cable, APC-7, 24-inch HP P/N 8120-4779
Calibration Kit, 7 mm HP 85031B

Required Equipment for 75Ω Analyzers

Cable, 75Ω, Type-N, 24-inch HP P/N 8120-2408
Calibration Kit, 75Ω, Type-N HP 85036B

Analyzer warm-up time: 1 hour

Perform this test to measure the return loss of each input test port.

2.76 System Verification and Performance Tests

1. Connect the equipment as shown in Figure 2-39.

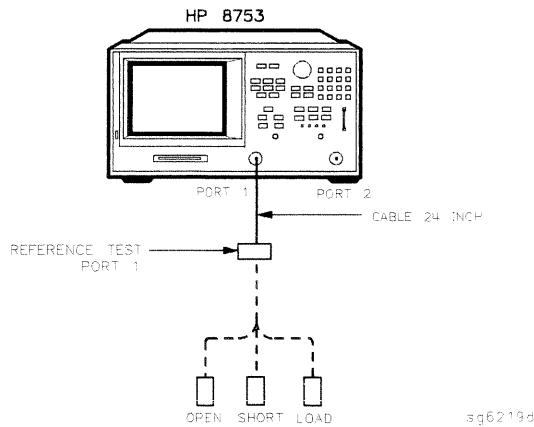


Figure 2-39. S11 1-Port Cal Test Setup

2. Press **[PRESET]** **[MENU]** **NUMBER of POINTS** **[1601]** **[x1]**.
3. **Only For Analyzers WITHOUT Option 006:** Press **[START]** **[50]** **[k/m]**.
4. Press **[CAL]** **CAL KIT** **SELECT CAL KIT** and select the appropriate calibration kit:
 - If your analyzer is 50Ω , press **CAL KIT: 7mm**.
 - If your analyzer is 75Ω , press **CAL KIT: N 75\Omega**.
5. Press **RETURN** **RETURN** **CALIBRATE MENU** **S11 1-PORT**.
6. Connect an open to reference test port 1, as shown in Figure 2-39.
7. Press **FORWARD: OPEN**.
8. When the analyzer displays the prompt **CONNECT STD THEN PRESS KEY TO MEASURE**, connect a short to reference test port 1.
9. Press **FORWARD: SHORT**.
10. At the prompt, connect a load to reference test port 1.
11. Press **FORWARD: LOAD**.

12. When the analyzer displays 'DONE' IF FINISHED WITH CAL, press **DONE 1-PORT CAL**.
13. Press **SAVE/RECALL** **SAVE STATE**.
14. Connect the equipment as shown in Figure 2-40.

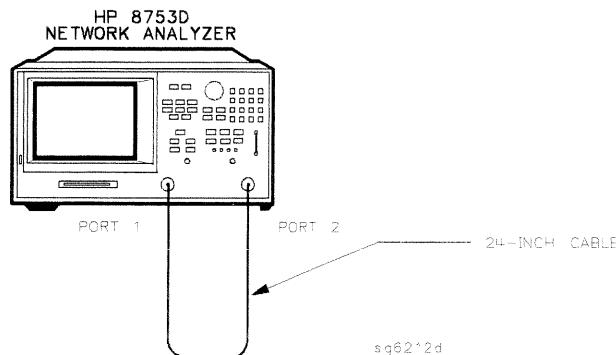


Figure 2-40. Test Port 2 Input Impedance Test Setup

15. Press **MARKER** to turn the analyzer's marker 1 on. Use the front panel knob to locate the maximum value of the data trace for each of the frequency ranges listed in the "Performance Test Record."
16. Write these maximum values on the "Performance Test Record."
17. Connect the equipment as shown in Figure 2-41.

2.78 System Verification and Performance Tests

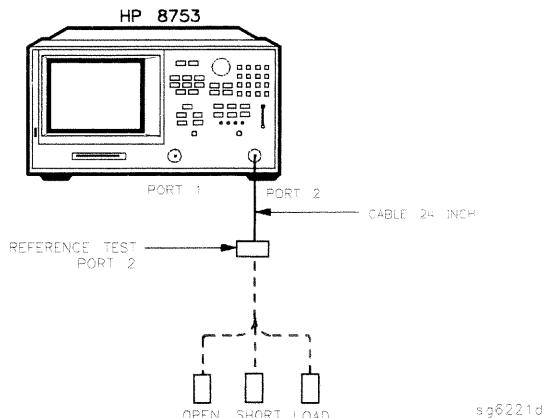


Figure 2-41. S22 1-Port Cal Test Setup

18. Press **CAL** CALIBRATE MENU S22 1-PORT .
19. At the prompt, connect an open to reference test port 2, as shown in Figure 2-41.
20. Press **REVERSE: OPEN** .
21. When the analyzer displays the prompt CONNECT STD THEN PRESS KEY TO MEASURE, connect a short to reference test port 2.
22. Press **REVERSE: SHORT** .
23. At the prompt, connect a load to reference test port 2.
24. Press **REVERSE: LOAD** .
25. When the analyzer displays 'DONE' IF FINISHED WITH CAL, press **DONE 1-PORT CAL** .
26. Press **SAVE/RECALL** SAVE STATE to save the 1-Port calibration.
27. Connect the equipment as shown in Figure 2-42.

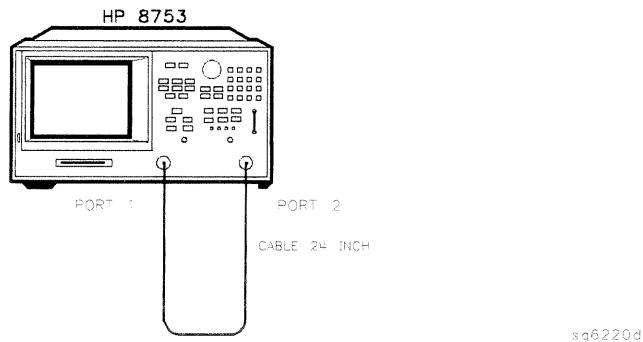


Figure 2-42. Test Port 1 Input Impedance Test Setup

28. Press **[MARKER]** to activate the analyzer's marker 1. Use the front panel knob to locate the maximum value of the data trace for each of the frequency ranges listed in the "Performance Test Record."
29. Write the maximum values on the "Performance Test Record."

In Case of Difficulty

1. Suspect the A10 digital IF board assembly if the analyzer fails BOTH test port tests.
2. Refer to the "Receiver Troubleshooting" chapter for more troubleshooting information.

2-80 System Verification and Performance Tests

13. Test Port Receiver Magnitude Dynamic Accuracy Specifications

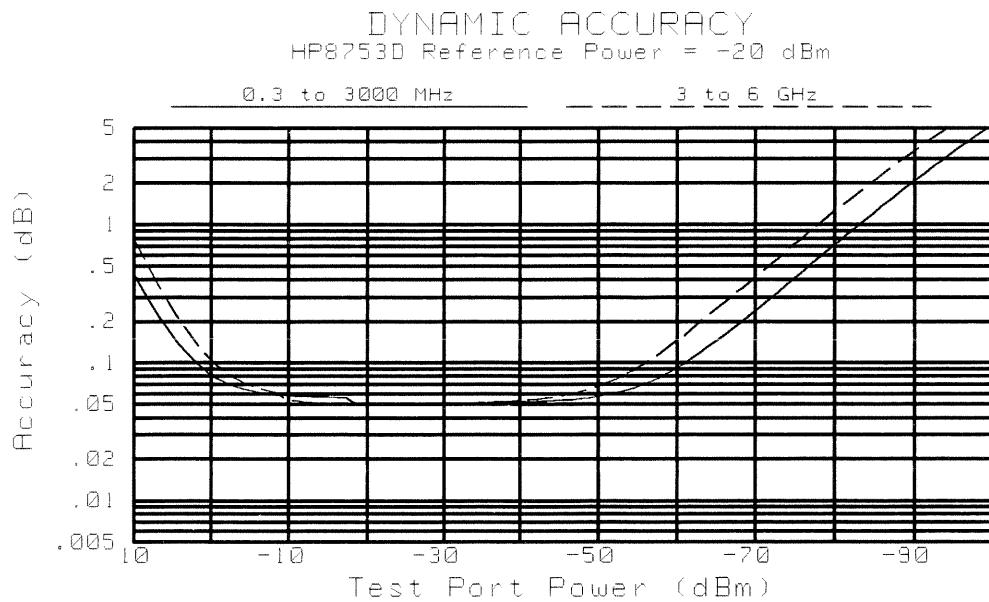


Figure 2-43. Receiver Magnitude Dynamic Accuracy

Required Equipment

Power Meter	HP 436A/437B/438A
Power Sensor	HP 8482A
Step Attenuator, 110 dB	HP 8496A Opt 001 (See note below.)
Adapter (2), APC-7 to Type-N (f)	HP 11524A
Adapter, Type-N (m) to Type-N (m)	HP P/N 1250-1528
2-Way Power Splitter, 50Ω, all ports Type-N (f)	HP 11667A
Cable (3), 50Ω, Type-N, 24-inch	HP P/N 8120-4781

Additional Required Equipment for 75Ω Analyzers

Minimum Loss Pad (2), 50Ω to 75Ω	HP 11852B
--	-----------

Note	The HP 8496A used for this test must have known attenuator errors for attenuations up to 100 dB using a test frequency of 30 MHz. The attenuation used as a reference is 0 dB.
-------------	--

Analyzer warm-up time: 1 hour

2-82 System Verification and Performance Tests

Test Port 2 Magnitude Dynamic Accuracy

Initial Calculations

1. Fill in the attenuator error values (referenced to 0 dB attenuation) in Table 2-1 (next page) by referring to the calibration data for the HP 8496A step-attenuator:
 - a. Find the column in the HP 8496A attenuation error table that pertains to the attenuation errors for 30 MHz.
 - b. Starting with the “10 dB” step in this column, write down the value in the corresponding space in Table 2-1 for column “B.” This value should be placed in the row for the 10 dB HP 8496A setting.
 - c. Continue transferring the remaining values of the HP 8496A attenuation errors to column “B” in Table 2-1.
2. In Table 2-1, transfer the 10 dB error value located within the parenthesis in column “B” to each space column “C.”

Table 2-1. Magnitude Dynamic Accuracy Calculations

A 8496A Attn. (dB)	B Attn. Error (ref 0 dB)	C 10 dB Error Value	D (B - C) Attn. Error (ref 10 dB)	E Expected Measurement (dBm)	F (E - D) Expected Measurement (corrected) (dBm)
0	0 dB	_____	_____	10	_____
10	(_____)	_____	0 dB	0	_____
20	_____	_____	_____	-10	_____
30	_____	_____	_____	-20	_____
40	_____	_____	_____	-30	_____
50	_____	_____	_____	-40	_____
60	_____	_____	_____	-50	_____
70	_____	_____	_____	-60	_____
80	_____	_____	_____	-70	_____
90	_____	_____	_____	-80	_____

3. The values in column "D" result from changing the reference attenuation of the calibration data of the HP 8496A to 10 dB.

Calculate the attenuation error values for this column by subtracting the values in column "C" from the values in column "B" ($B - C = D$).

4. The values in column "F" result from correcting the expected measurement value by the amount of attenuator error.

Calculate the values in this column by subtracting the values in column "D" from the values in column "E" ($E - D = F$).

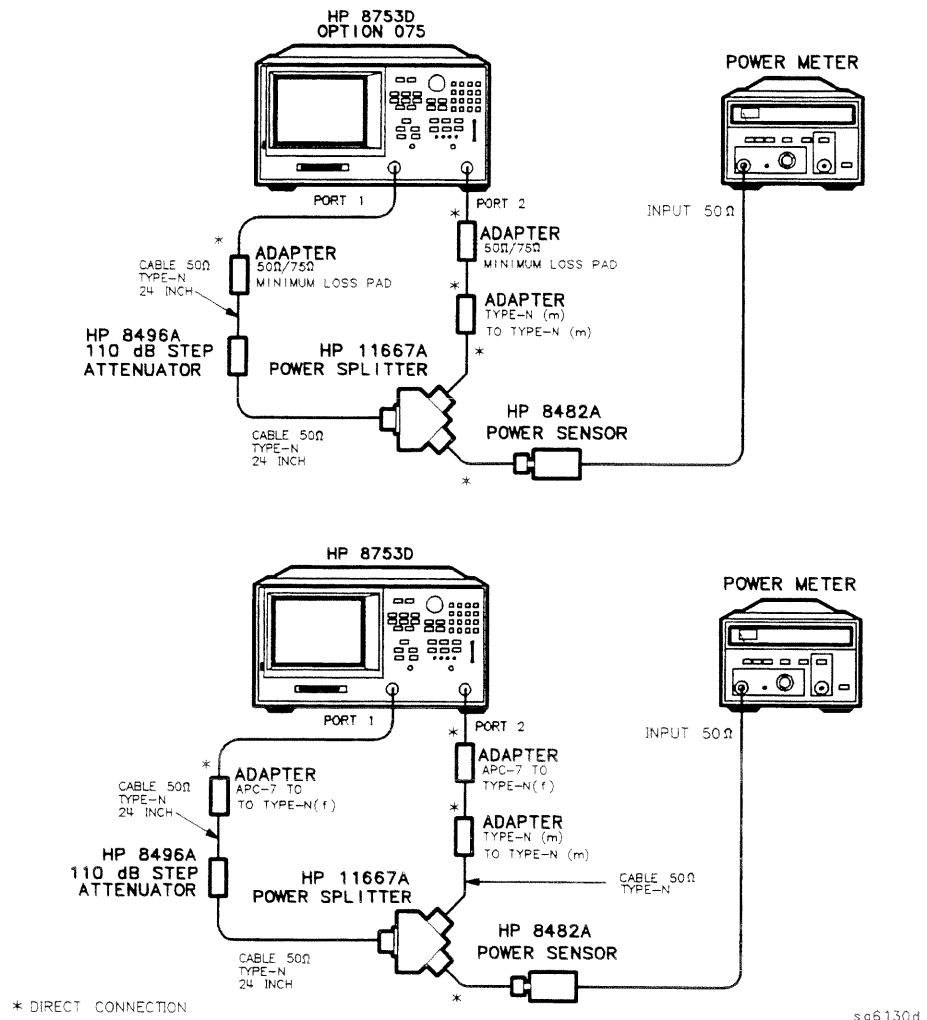
5. Transfer the values from column "F" in Table 2-1 to column "F" in the "Performance Test Record" for both test ports.

Setup and Measurements

6. Zero and calibrate the power meter. (Refer to the power meter manual for details on this procedure.)
7. Set the power meter for the 30 MHz cal factor imprinted on the HP 8482A power sensor.

2-84 System Verification and Performance Tests

8. Connect the equipment as shown in Figure 2-44.



sg6130d

Figure 2-44. Test Port 2 Dynamic Accuracy Test Setup

9. Set the HP 8496A to 10 dB.

10. Set the following analyzer parameters:

Press [PRESET] [MENU] CW FREQ [30] [M/ μ]
NUMBER of POINTS [51] [x1]
[AVG] IF BW [10] [x1].

11. Press [MEAS] INPUT PORTS B [MENU] POWER [-4] [x1].
12. Using the analyzer front panel knob, adjust the test port power for a reading of -20.000 dBm on the power meter.
13. Choose the appropriate power meter range and resolution. Wait for the reading to stabilize.
14. Press [CAL] CALIBRATE MENU RESPONSE THRU
[SAVE/RECALL] SAVE STATE .
15. Press [MARKER FCTN] MARKER MODE MENU STATS ON .
16. Set the HP 8496A to 0 dB.
17. Press [MENU] TRIGGER MENU SINGLE .
18. Write the mean value (which appears on the analyzer's display) in the "Test Port Measurement" column of the "Performance Test Record." This column is also labeled "G."
19. Repeat steps 16 through 18 for each setting of the step attenuator.
20. Calculate dynamic accuracy for each step by using the formula $|G - F|$. Place these values in the appropriate column of the "Performance Test Record."

Test Port 1 Magnitude Dynamic Accuracy

21. Set the HP 8496A to 10 dB.
22. Press CONTINUOUS **MEAS** INPUT PORTS TESTPORT 2 A.
23. Connect the equipment as shown in Figure 2-45.

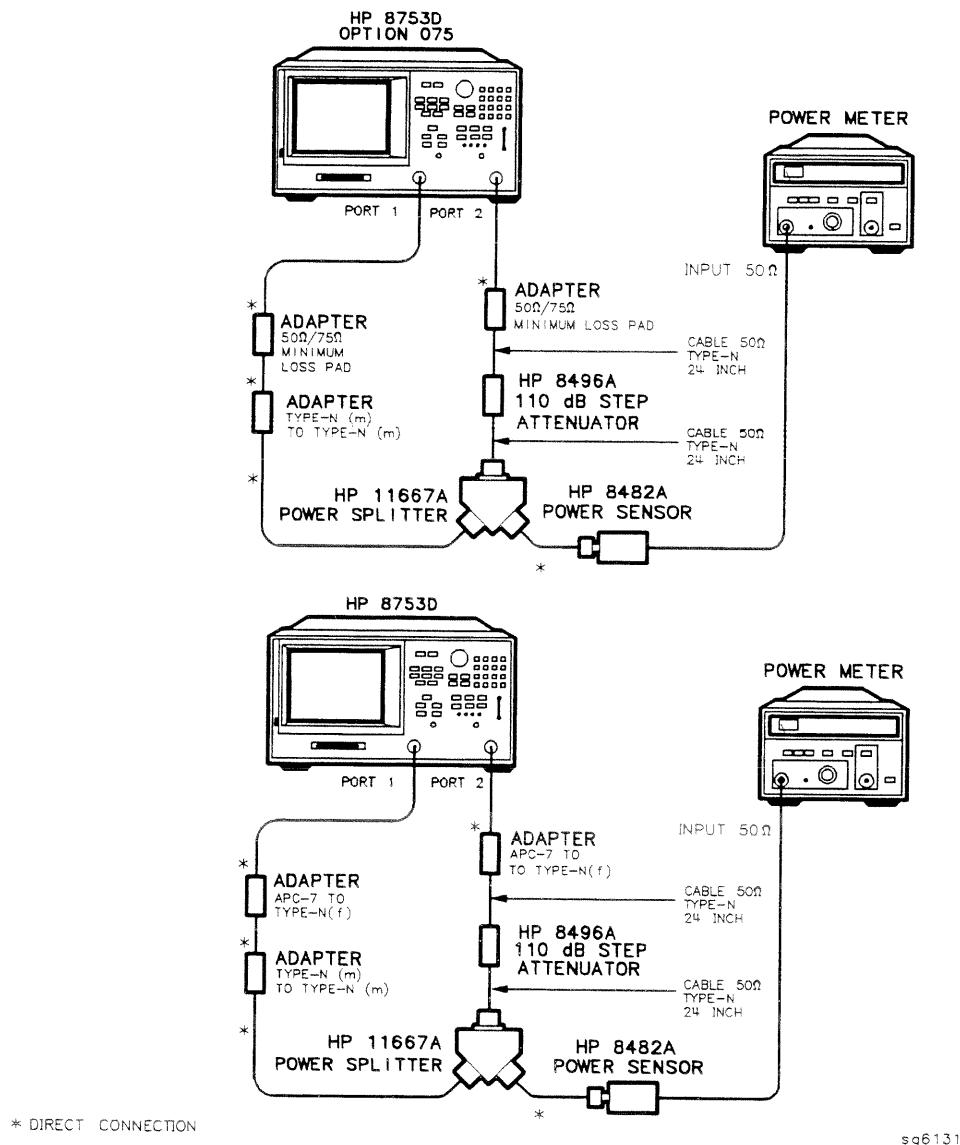


Figure 2-45. Test Port 1 Magnitude Dynamic Accuracy Test Setup

24. Press **[MENU] POWER**.

2-88 System Verification and Performance Tests

25. Using the analyzer front panel knob, adjust the test port power for a reading of -20.000 dBm on the power meter.
26. Wait for the reading to stabilize.
27. Press **CAL** CALIBRATE MENU RESPONSE THRU
SAVE/RECALL SAVE STATE .
28. Press **MARKER FCTN** MARKER MODE MENU STATS ON .
29. Set the HP 8496A to 0 dB.
30. Press **MENU** TRIGGER MENU SINGLE .
31. Write the mean value (which appears on the analyzer's display) in the "Test Port Measurement" column of the "Performance Test Record." This column is also labeled "G."
32. Repeat steps 29 through 31 for each setting of the step attenuator.
33. Calculate dynamic accuracy for each step by using the formula $|G - F|$. Place these values in the appropriate column of the "Performance Test Record."

In Case of Difficulty

1. If the analyzer fails the test at ALL power levels, be sure you followed the recommended attenuator settings as listed in the “Performance Test Record.” Repeat this performance test.
2. If both test port measured values are out of specifications:
 - a. Recalibrate the power meter.
 - b. Repeat this performance test.
3. If the analyzer fails either test port 2 or test port 1 dynamic accuracy at lower power levels:
 - a. Perform the “IF Amplifier Correction Constants” and “ADC Offset Correction Constants” procedures (located in the “Adjustments and Correction Constants” chapter).
 - b. Repeat this performance test.
 - c. If it still fails, replace the A10 Digital IF assembly.
 - d. Repeat the two adjustment procedures mentioned in this step and then repeat the this performance test.

14. Test Port Receiver Phase Dynamic Accuracy

Specification

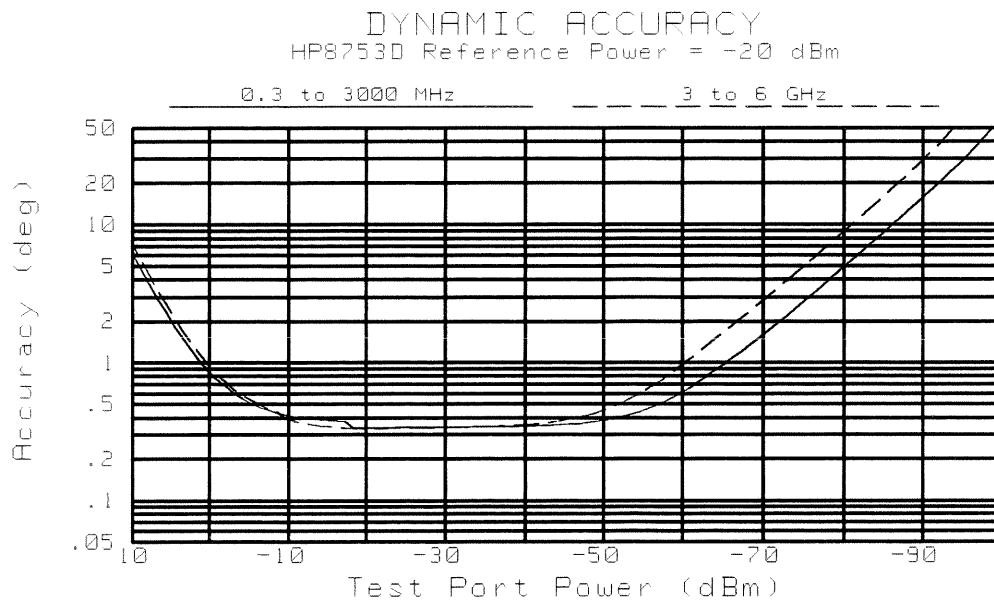


Figure 2-46. Dynamic Accuracy (Phase)

Test Port 2 Phase Dynamic Accuracy

1. Refer to the "Test Port Receiver Magnitude Dynamic Accuracy" portion of the "Performance Test Record," for the values in the "Calculated Value" column.
2. Copy the values in the "Magnitude Value" column to the "Calculated Value" column of the "Test Port Receiver Phase Dynamic Accuracy" portion of the "Performance Test Record."
3. For every test port input power level, calculate "A" using the following formula:

$$A = 10\left(\frac{\text{Calculated Value}}{20}\right)$$

4. Write the result in the "A" column of the "Performance Test Record."

5. For every test port input power level, calculate “B” using the following formula:

$$B = 1 - A$$

6. Write the result in the “B” column of the “Performance Test Record.”
7. For every test port input power level, calculate the receiver phase dynamic accuracy using the following formula:

$$\text{Phase Dynamic Accuracy} = \text{SIN}^{-1} (B)$$

8. Write the value in the “Results Value” column of the “Performance Test Record.”

Test Port 1 Phase Dynamic Accuracy

9. Repeat steps 1 to 8.

15. Test Port Receiver Magnitude Compression Specifications

Frequency Range	Test Port	Magnitude¹
300 kHz to 3 GHz	Port 1	≤ 0.45 dB
3 GHz to 6 GHz ²	Port 1	≤ 0.80 dB
300 kHz to 3 GHz	Port 2	≤ 0.45 dB
3 GHz to 6 GHz ²	Port 2	≤ 0.80 dB

1 With a 10 Hz IF bandwidth.

2 Only for analyzers with Option 006.

Required Equipment for 50Ω Analyzers

Cable, APC-7, 24-inch HP P/N 8120-4779

Required Equipment for 75Ω Analyzers

Cable, 75Ω, Type-N, 24-inch HP P/N 8120-2408

Analyzer warm-up time: 1 hour

Perform this test to verify the compression/expansion magnitude levels of the analyzer's test port receiver samplers.

Test Port 2 Magnitude Compression

1. Connect the equipment as shown in Figure 2-47.

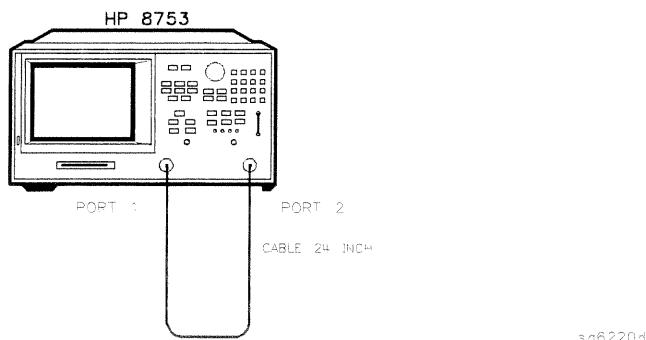


Figure 2-47. Test Port Magnitude Compression Test Setup

2. Press [PRESET] [MEAS] Trans: FWD S21 (B/R).
3. Press [AVG] IF BW [10] [x1].
4. Press [MENU] CW FREQ [50] [M/ μ].
5. Press SWEEP TYPE MENU POWER SWEEP START [-10] [x1].
6. Press [MENU] TRIGGER MENU SINGLE.
7. At the end of the sweep, press [SCALE REF] AUTO SCALE.
8. Press [MARKER FCTN] MKR SEARCH SEARCH: MAX.
9. Press [MARKER] MARKER 2 [MARKER FCTN] MKR SEARCH SEARCH: MIN.
10. Press [MARKER] ΔMODE MENU ΔREF = 1.
11. Write the absolute value of the marker 2 reading in the "Performance Test Record."
12. Press [MENU] CW FREQ [1] [G/n].
13. Press TRIGGER MENU SINGLE.
14. At the end of the sweep, press [SCALE REF] AUTO SCALE.

2-94 System Verification and Performance Tests

15. Press **MARKER** MARKER AREF=1 **MARKER FCTN** MKR SEARCH SEARCH: MAX.
16. Press **MARKER** MARKER 2 **MARKER FCTN** MKR SEARCH SEARCH: MIN.
17. Write the absolute value of marker 2 in the “Performance Test Record.”
18. Repeat steps 12 through 17 for the other frequencies listed for Port 2 on the “Performance Test Record.”

Test Port 1 Magnitude Compression

19. Press **MEAS** Trans: REV S12 (A/R).
20. Press **MENU** CW FREQ **50 M/ μ** .
21. Press TRIGGER MENU SINGLE.
22. At the end of the sweep, press **SCALE REF** AUTO SCALE .
23. Press **MARKER** MARKER AREF = 1 **MARKER FCTN** MKR SEARCH SEARCH: MAX.
24. Press **MARKER** MARKER 2 **MARKER FCTN** MKR SEARCH SEARCH: MIN.
25. Write the absolute value of the marker 2 reading in the “Measured Value” column of the “Performance Test Record.”
26. Repeat steps 19 through 25 for the other CW frequencies listed for Port 1 in the “Performance Test Record.”

In Case of Difficulty

1. If the analyzer fails “Test Port 2 Magnitude Compression”:
 - a. Repeat this test.
 - b. Replace the A6 B sampler assembly if the analyzer still fails the test.
2. If the analyzer fails “Test Port 1 Magnitude Compression”:
 - a. Repeat this test.
 - b. Replace the A5 A sampler assembly if the analyzer still fails the test.

16. Test Port Receiver Phase Compression

Specifications

CW Frequency	Test Port	Phase ¹
300 kHz to 3 GHz	Port 1	$\leq 6^\circ$
3 GHz to 6 GHz ²	Port 1	$\leq 7.5^\circ$
300 kHz to 3 GHz	Port 2	$\leq 6^\circ$
3 GHz to 6 GHz ²	Port 2	$\leq 7.5^\circ$

1 With 10 Hz IF bandwidth.

2 Only for analyzer with Option 006.

Required Equipment for 50Ω Analyzers

Cable, APC-7, 24-inch HP P/N 8120-4779

Required Equipment for 75Ω Analyzers

Cable, 75Ω, Type-N, 24-inch HP P/N 8120-2408

Analyzer warm-up time: 1 hour

Perform this test to verify the compression/expansion phase relationships of the analyzer's test port receiver samplers.

Test Port 2 Phase Compression

1. Connect the equipment as shown in Figure 2-48.

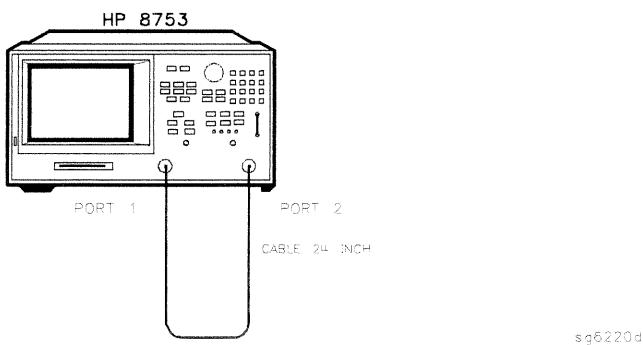


Figure 2-48. Test Port Phase Compression Test Setup

2. Press [PRESET] [MEAS] Trans: FWD S21 (B/R) [FORMAT] PHASE .
3. Press [AVG] IF BW [10] [x1].
4. Press [MENU] SWEEP TYPE MENU POWER SWEEP [START] [-10] [x1].
5. Press [MENU] CW FREQ [50] [M/ μ]
6. Press [MENU] TRIGGER MENU SINGLE .
7. At the end of the sweep, press [SCALE REF] AUTO SCALE .
8. Press [MARKER FCTN] MKR SEARCH SEARCH: MAX .
9. Press [MARKER] MARKER 2 [MARKER FCTN] MKR SEARCH SEARCH: MIN .
10. Press [MARKER] ΔMODE MENU ΔREF = 1 .
11. Write the absolute value of the marker 2 reading in the "Measured Value" column of the "Performance Test Record."
12. Repeat steps 5 to 11 for the other CW frequencies listed for Port 2 in the "Performance Test Record."

Test Port 1 Phase Compression

13. Press [MEAS] Trans: REV S12 (A/R) [FORMAT] PHASE .
14. Press [MENU] CW FREQ [50] [M/ μ]
15. Press [MENU] TRIGGER MENU SINGLE .
16. At the end of the sweep, press [SCALE REF] AUTO SCALE .
17. Press [MARKER] MARKER AREF = 1 [MARKER FCTN] MKR SEARCH SEARCH: MAX .
18. Press [MARKER] MARKER 2 [MARKER FCTN] MKR SEARCH SEARCH: MIN .
19. Write the absolute value of the marker 2 reading in the "Measured Value" column of the "Performance Test Record."
20. Repeat steps 14 to 19 for the other CW frequencies listed for Port 1 in the "Performance Test Record."

In Case of Difficulty

1. If the analyzer fails the "Test Port 2 Phase Compression" test:
 - a. Repeat this test.
 - b. Replace the A6 B sampler assembly if analyzer still fails the test.
2. If the analyzer fails the "Test Port 1 Phase Compression" test:
 - a. Repeat this test.
 - b. Replace the A5 A sampler assembly if analyzer still fails the test.

17. Test Port Output/Input Harmonics (Option 002 Analyzers without Option 006 Only)

Specifications

Test Port	Harmonic	Limit
Output	2nd	< -25 dBc @ +10 dBm
Output	3rd	< -25 dBc @ +10 dBm
Input Port 1	2nd	< -15 dBc @ +8 dBm
Input Port 1	3rd	< -30 dBc @ +8 dBm
Input Port 2	2nd	< -15 dBc @ +8 dBm
Input Port 2	3rd	< -30 dBc @ +8 dBm

Equipment Required for 50Ω Analyzers

Cable, APC-7, 24-inch HP P/N 8120-4779
Attenuator (2), 20 dB, APC-7 HP 8492A Opt 020

Equipment Required for 75Ω Analyzers

Minimum Loss Pad (2) HP 11852B
Cable, Type-N HP P/N 8120-2408
Attenuator (2), 20 dB, Type-N HP 8491A Opt 020

Analyzer warm-up time: 30 minutes

Perform this test to determine the spectral purity of the HP 8753D input and output test ports.

Note

The test port input 3rd harmonic specifications are *better* than the test port output 3rd harmonic specifications.

Test Port Output Worst Case 2nd Harmonic

1. Press [PRESET] [MENU] POWER [10] [x1].
2. Press [START] [16] [M/ μ] [STOP] [1.5] [G/n] to set the frequency range.
3. Press [AVG] IF BW [10] [x1] to set the IF bandwidth to 10 Hz.
4. Connect the equipment as shown in Figure 2-49.

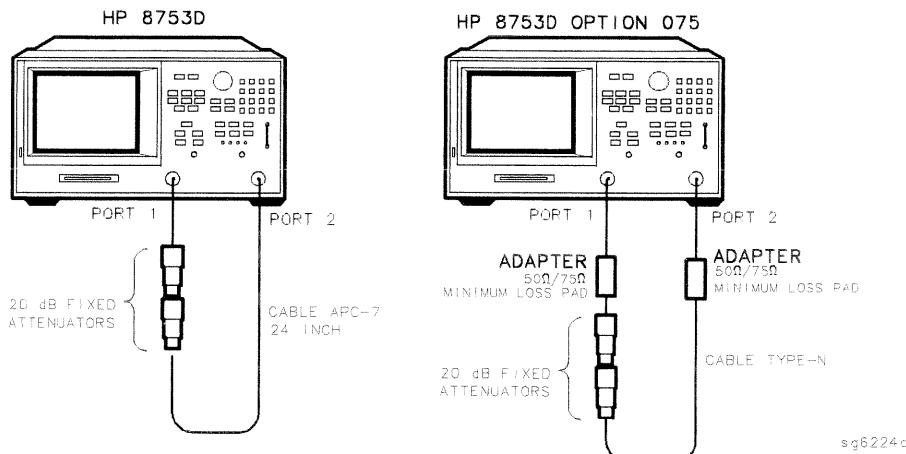


Figure 2-49. Test Port Output Harmonics Test Setup

5. Press [MEAS] Trans:REV S12 (A/R) INPUT PORTS A.
6. After one sweep, press [DISPLAY] DATA—MEMORY DATA/MEM to normalize the trace.
7. Press [SYSTEM] HARMONIC MEAS HARMONIC SECOND.
8. After one sweep, press [SCALE REF] AUTO SCALE to get a better viewing of the trace.
9. Press [MARKER FCTN] MKR SEARCH SEARCH MAX.
10. Write the marker 1 value (which appears on the analyzer display) on the "Performance Test Record." This is the worst case test port output 2nd harmonic.

2-100 System Verification and Performance Tests

Test Port Output Worst Case 3rd Harmonic

11. Press **STOP** **1** **G/n** to change the stop frequency to 1 GHz.
12. Press **SYSTEM** **HARMONIC MEAS HARMONIC OFF**.
13. After one sweep, press **DISPLAY** **DATA—MEMORY DATA/MEM** to normalize the trace.
14. Press **SCALE REF** **AUTO SCALE SCALE/DIV** **1** **x1** to get a better viewing of the trace.
15. Press **SYSTEM** **HARMONIC MEAS HARMONIC THIRD**.
16. After one sweep, press **SCALE REF** **AUTO SCALE**.
17. Press **MARKER FCTN** **MKR SEARCH SEARCH MAX**.
18. Write the marker 1 value on the “Performance Test Record.”

Port 1 Input Worst Case 2nd Harmonic

19. Connect the equipment as shown in Figure 2-50.

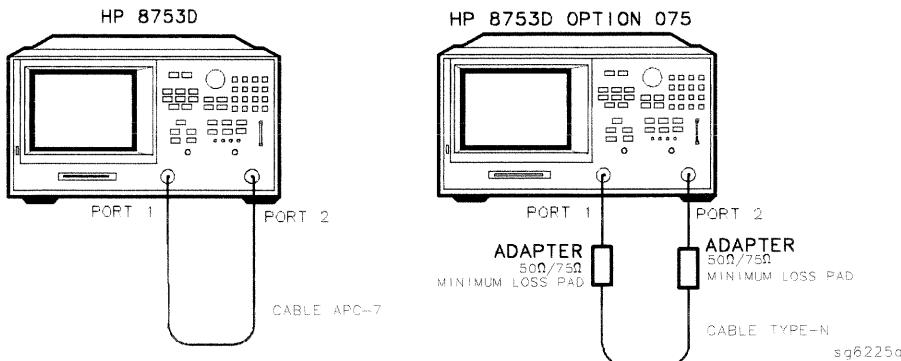


Figure 2-50. Receiver Harmonics Test Setup

20. Press **PRESET** **MENU** **POWER** **8** **x1**.
21. Press **AVG** **IF BW** **1** **0** **x1**.

22. Press **START** **16** **M/ μ** **STOP** **1.5** **G/n** to set the frequency range.
23. Press **MEAS** **Trans:REV S12 (A/R)** **INPUT PORTS A**.
24. After one sweep, press **DISPLAY** **DATA→MEMORY DATA/MEM** to normalize the trace.
25. Press **SYSTEM** **HARMONIC MEAS HARMONIC SECOND**.
26. After one sweep, press **SCALE REF** **AUTO SCALE** to get a better viewing of the trace.
27. Press **MARKER FCTN** **MKR SEARCH SEARCH MAX**.
28. Write the marker 1 value (which appears on the analyzer display) on the “Performance Test Record.” This is the worst case port 1 input (receiver channel A) 2nd harmonic.

Port 1 Input Worst Case 3rd Harmonic

29. Press **STOP** **1** **G/n** to change the stop frequency for measuring the receiver 3rd harmonic.
30. Press **SYSTEM** **HARMONIC MEAS HARMONIC OFF**.
31. After one sweep, press **DISPLAY** **DATA→MEMORY DATA/MEM** to normalize the trace.
32. Press **SCALE REF** **AUTO SCALE** **SCALE/DIV 1 x1** to get a better viewing of the trace.
33. Press **SYSTEM** **HARMONIC MEAS HARMONIC THIRD**.
34. After one sweep, press **SCALE REF** **AUTO SCALE**.
35. Press **MARKER FCTN** **MKR SEARCH SEARCH MAX**.
36. Write the marker 1 value on the “Performance Test Record.”
37. Press **SYSTEM** **HARMONIC MEAS HARMONIC OFF**.

2.102 System Verification and Performance Tests

Port 2 Input Worst Case 2nd Harmonic

38. Press **STOP** **1.5** **G/n** to set the stop frequency for measuring the 2nd harmonic.
39. Press **MEAS** **Trans:FWD S21 (B/R)** **INPUT PORTS B**.
40. After one sweep, press **DISPLAY** **DATA→MEMORY DATA/MEM** to normalize the trace.
41. Press **SYSTEM** **HARMONIC MEAS HARMONIC SECOND**.
42. After one sweep, press **SCALE REF** **AUTO SCALE** to get a better viewing of the trace.
43. Press **MARKER FCTN** **MKR SEARCH SEARCH MAX**.
44. Write the marker 1 value (which appears on the analyzer display) on the “Performance Test Record.” This is the worst case port 2 input (receiver channel B) 2nd harmonic.

Port 2 Input Worst Case 3rd Harmonic

45. Press **STOP** **1** **G/n** to change the stop frequency for measuring the receiver 3rd harmonic.
46. Press **SYSTEM** **HARMONIC MEAS HARMONIC OFF**.
47. After one sweep, press **DISPLAY** **DATA→MEMORY DATA/MEM** to normalize the trace.
48. Press **SCALE REF** **AUTO SCALE** **SCALE/DIV 1 x1** to get a better viewing of the trace.
49. Press **SYSTEM** **HARMONIC MEAS HARMONIC THIRD**.
50. After one sweep, press **SCALE REF** **AUTO SCALE**.
51. Press **MARKER FCTN** **MKR SEARCH SEARCH MAX**.
52. Write the marker 1 value on the “Performance Test Record.”

18. Test Port Output/Input Harmonics (Option 002 Analyzers with Option 006 Only)

Specifications

Test Port	Harmonic	Limit
Output	2nd	< -25 dBc @ +10 dBm
Output	3rd	< -25 dBc @ +10 dBm
Input Port 1	2nd	< -15 dBc @ +8 dBm
Input Port 1	3rd	< -30 dBc @ +8 dBm
Input Port 2	2nd	< -15 dBc @ +8 dBm
Input Port 2	3rd	< -30 dBc @ +8 dBm

Equipment Required

Cable, APC-7, 24-inch HP P/N 8120-4779
Attenuator (2), 20 dB HP 8492A Opt 020

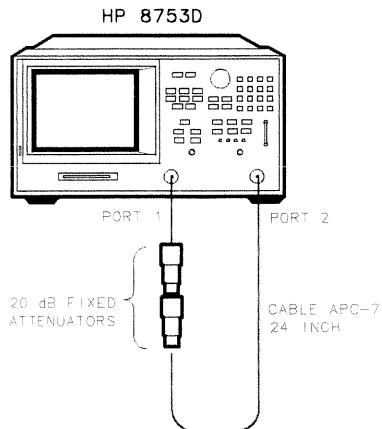
Analyzer warm-up time: 30 minutes

Perform this test to determine the spectral purity of the HP 8753D input and output test ports.

Note The test port input 3rd harmonic specifications are *better* than the test port output 3rd harmonic specifications.

Test Port Output Worst Case 2nd Harmonic

1. Press **PRESET** **MENU** **POWER** **10** **x1** to set the test port power to +10 dBm.
2. Press **START** **16** **M/ μ** **STOP** **3** **G/n** to set the frequency range.
3. Press **AVG** **IF BW** **10** **x1** to set the IF bandwidth to 10 Hz.
4. Connect the equipment as shown in Figure 2-51.



Xg68d

Figure 2-51. Test Port Output Harmonics Test Setup

5. Press **MEAS** **Trans:REV S12 (A/R)** **INPUT PORTS A**.
6. After one sweep, press **DISPLAY** **DATA—MEMORY DATA/MEM** to normalize the trace.
7. Press **SYSTEM** **HARMONIC MEAS HARMONIC SECOND**.
8. After one sweep, press **SCALE REF** **AUTO SCALE** to get a better viewing of the trace.
9. Press **MARKER FCTN** **MKR SEARCH SEARCH MAX**.

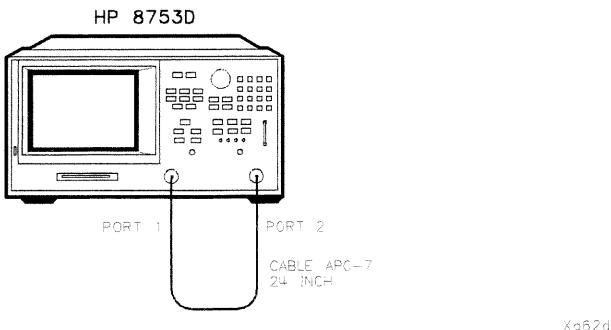
10. Write the marker 1 value (which appears on the analyzer display) on the “Performance Test Record.” This is the worst case test port output 2nd harmonic.

Test Port Output Worst Case 3rd Harmonic

11. Press **STOP** **2** **G/n** to change the stop frequency to 1 GHz.
12. Press **SYSTEM** **HARMONIC MEAS HARMONIC OFF**.
13. After one sweep, press **DISPLAY** **DATA—MEMORY DATA/MEM** to normalize the trace.
14. Press **SCALE REF** **AUTO SCALE** **SCALE/DIV** **1** **x1** to get a better viewing of the trace .
15. Press **SYSTEM** **HARMONIC MEAS HARMONIC THIRD**.
16. After one sweep, press **SCALE REF** **AUTO SCALE**.
17. Press **MARKER FCTN** **MKR SEARCH** **SEARCH MAX**.
18. Write the marker 1 value on the “Performance Test Record.”

Port 1 Input Worst Case 2nd Harmonic

19. Connect the equipment as shown in Figure 2-52.



X962d

Figure 2-52. Receiver Harmonics Test Setup

20. Press [PRESET] [MENU] POWER [8] [x1].
21. Press [AVG] IF BW [10] [x1].
22. Press [START] [16] [M/u] [STOP] [3] [G/n] to set the frequency range.
23. Press [MEAS] Trans:REV S12 (A/R) INPUT PORTS A.
24. After one sweep, press [DISPLAY] DATA—MEMORY DATA/MEM to normalize the trace.
25. Press [SYSTEM] HARMONIC MEAS HARMONIC SECOND.
26. After one sweep, press [SCALE REF] AUTO SCALE to get a better viewing of the trace.
27. Press [MARKER FCTN] MKR SEARCH SEARCH: MAX.
28. Write the marker 1 value (which appears on the analyzer display) on the "Performance Test Record." This is the worst case port 1 input (receiver channel A) 2nd harmonic.

Port 1 Input Worst Case 3rd Harmonic

29. Press **STOP** **2** **G/n** to change the stop frequency for measuring the receiver 3rd harmonic.
30. Press **SYSTEM** **HARMONIC MEAS** **HARMONIC OFF**.
31. After one sweep, press **DISPLAY** **DATA→MEMORY** **DATA/MEM** to normalize the trace.
32. Press **SCALE REF** **AUTO SCALE** **SCALE/DIV** **1** **x1** to get a better viewing of the trace.
33. Press **SYSTEM** **HARMONIC MEAS** **HARMONIC THIRD**.
34. After one sweep, press **SCALE REF** **AUTO SCALE**.
35. Press **MARKER FCTN** **MKR SEARCH** **SEARCH: MAX**.
36. Write the marker 1 value on the “Performance Test Record.”
37. Press **SYSTEM** **HARMONIC MEAS** **HARMONIC OFF**.

Port 2 Input Worst Case 2nd Harmonic

38. Press **STOP** **3** **G/n** to set the stop frequency for measuring the 2nd harmonic.
39. Press **MEAS** **Trans:FWD S21 (B/R)** **INPUT PORTS B**.
40. After one sweep, press **DISPLAY** **DATA→MEMORY** **DATA/MEM** to normalize the trace.
41. Press **SYSTEM** **HARMONIC MEAS** **HARMONIC SECOND**.
42. After one sweep, press **SCALE REF** **AUTO SCALE** to get a better viewing of the trace.
43. Press **MARKER FCTN** **MKR SEARCH** **SEARCH MAX**.
44. Write the marker 1 value (which appears on the analyzer display) on the “Performance Test Record.” This is the worst case port 2 input (receiver channel B) 2nd harmonic.

Port 2 Input Worst Case 3rd Harmonic

45. Press **STOP** **2** **G/n** to change the stop frequency for measuring the receiver 3rd harmonic.
46. Press **SYSTEM** **HARMONIC MEAS** **HARMONIC OFF**.
47. After one sweep, press **DISPLAY** **DATA—MEMORY** **DATA/MEM** to normalize the trace.
48. Press **SCALE REF** **AUTO SCALE** **SCALE/DIV** **(1)** **x1** to get a better viewing of the trace.
49. Press **SYSTEM** **HARMONIC MEAS** **HARMONIC THIRD**.
50. After one sweep, press **SCALE REF** **AUTO SCALE**.
51. Press **MARKER FCTN** **MKR SEARCH** **SEARCH: MAX**.
52. Write the marker 1 value on the “Performance Test Record.”

2a

Performance Test Record

For Analyzers with a Frequency Range of
30 kHz to 3 GHz

Note

See the next “Performance Test Record” section if your analyzer frequency range is from 30 kHz to 6 GHz (Option 006).

HP 8753D Performance Test Record (1 of 13)

Calibration Lab Address:	Report Number _____
	Date _____
	Last Calibration Date _____
	Customer's Name _____
	Performed by _____

Model HP 8753D

Serial No. _____ Option(s) _____

Firmware Revision _____

Ambient Temperature _____ °C Relative Humidity _____ %

Test Equipment Used:

Description	Model Number	Trace Number	Cal Due Date
-------------	--------------	--------------	--------------

Frequency Counter	_____	_____	_____
-------------------	-------	-------	-------

Power Meter	_____	_____	_____
-------------	-------	-------	-------

Power Sensor	_____	_____	_____
--------------	-------	-------	-------

Calibration Kit	_____	_____	_____
-----------------	-------	-------	-------

Verification Kit	_____	_____	_____
------------------	-------	-------	-------

Notes/Comments: _____

HP 8753D Performance Test Record (2 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____			
Serial Number _____	Date _____			
►► 1. Test Port Output Frequency Range and Accuracy				
CW Frequencies (MHz)	Min. (MHz)	Results Measured (MHz)	Max. (MHz)	Measurement Uncertainty (MHz)
0.03	0.029 999 7	_____	0.030 000 3	± 0.000 000 050
0.3	0.299 997	_____	0.300 003	± 0.000 000 520
5.0	4.999 950	_____	5.000 050	± 0.000 009
16.0	15.999 840	_____	16.000 160	± 0.000 028
31.0	30.999 690	_____	31.000 310	± 0.000 054
60.999 999	60.999 390	_____	61.000 610	± 0.000 105
121.0	120.998 790	_____	121.001 210	± 0.000 207
180.0	179.998 200	_____	180.001 800	± 0.000 307
310.0	309.995 900	_____	310.003 100	± 0.000 528
700.0	699.930 000	_____	700.007 000	± 0.001 192
1 300.0	1 299.987	_____	1 300.013	± 0.002 212
2 000.0	1 999.980	_____	2 000.020	± 0.003 403
3 000.0	2 999.970	_____	3 000.030	± 0.005 104
►► 2. External Source Mode Frequency Range				
Test Frequencies (GHz)	Results			
0.010	_____	_____	_____	_____
0.020	_____	_____	_____	_____
0.100	_____	_____	_____	_____
1.000	_____	_____	_____	_____
2.000	_____	_____	_____	_____
3.000	_____	_____	_____	_____

HP 8753D Performance Test Record (3 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D		Report Number _____		
Serial Number _____		Date _____		
►► 3. Test Port Output Power Accuracy				
Test Frequencies	Test Port Output Power (dBm)	Specification (dB)	Measured Value (dB)	Measurement Uncertainty (dB)
Center Frequency				
300 kHz	0	± 1	_____	± 0.465
20 MHz	0	± 1	_____	± 0.10
50 MHz	0	± 1	_____	± 0.10
100 MHz	0	± 1	_____	± 0.10
200 MHz	0	± 1	_____	± 0.10
500 MHz	0	± 1	_____	± 0.10
1 GHz	0	± 1	_____	± 0.13
2 GHz	0	± 1	_____	± 0.13
3 GHz	0	± 1	_____	± 0.27
►► 4. Test Port Output Power Range and Linearity				
Test Settings	Results Measured (dB)	Power Level Linearity (dB)	Specification (dB)	Measurement Uncertainty (dB)
CW Frequency = 300 kHz				
- 15	_____	_____	± 0.2	± 0.03
- 13	_____	_____	± 0.2	± 0.03
- 11	_____	_____	± 0.2	± 0.03
- 9	_____	_____	± 0.2	± 0.02
- 7	_____	_____	± 0.2	± 0.02
- 5	_____	_____	± 0.2	± 0.02
- 3	_____	_____	± 0.2	± 0.02
- 1	_____	_____	± 0.2	± 0.02
+ 1	_____	_____	± 0.2	± 0.03
+ 3	_____	_____	± 0.2	± 0.03
+ 5	_____	_____	± 0.5	± 0.03

2a-4 Performance Test Record

HP 8753D Performance Test Record (4 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____			
Serial Number _____	Date _____			
►► 4. Test Port Output Power Range and Linearity (continued)				
Test Settings	Results Measured (dB)	Power Level Linearity (dB)	Specification (dB)	Measurement Uncertainty (dB)
+ 7	_____	_____	± 0.5	± 0.03
+ 9	_____	_____	± 0.5	± 0.03
+ 10	_____	_____	± 0.5	± 0.03
CW Frequency = 3 GHz				
- 15	_____	_____	± 0.2	± 0.03
- 13	_____	_____	± 0.2	± 0.03
- 11	_____	_____	± 0.2	± 0.03
- 9	_____	_____	± 0.2	± 0.02
- 7	_____	_____	± 0.2	± 0.02
- 5	_____	_____	± 0.2	± 0.02
- 3	_____	_____	± 0.2	± 0.02
- 1	_____	_____	± 0.2	± 0.02
+ 1	_____	_____	± 0.2	± 0.03
+ 3	_____	_____	± 0.2	± 0.03
+ 5	_____	_____	± 0.5	± 0.03
+ 7	_____	_____	± 0.5	± 0.03
+ 9	_____	_____	± 0.5	± 0.03
+ 10	_____	_____	± 0.5	± 0.03

HP 8753D Performance Test Record (5 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D		Report Number _____			
Serial Number _____		Date _____			
►► 5. Minimum R Channel Level					
CW Frequency	Specification (dB)	Test Port Power	Measurement Uncertainty (dB)		
300 kHz	< -35	_____	± 1.0		
3.29 MHz	< -35	_____	± 1.0		
3.31 MHz	< -35	_____	± 1.0		
15.90 MHz	< -35	_____	± 1.0		
16.10 MHz	< -35	_____	± 1.0		
30.90 MHz	< -35	_____	± 1.0		
31.10 MHz	< -35	_____	± 1.0		
1.6069 GHz	< -35	_____	± 1.0		
1.6071 GHz	< -35	_____	± 1.0		
3.000 GHz	< -35	_____	± 1.0		
►► 6. Test Port Input Noise Floor Level					
Frequency Range	Test Port	IF Bandwidth	Specification (dBm)	Calculated Value	Measurement Uncertainty
Frequency Range	Test Port	IF Bandwidth	Specification (dBm)	Calculated Value	Measurement Uncertainty
300 kHz - 3 GHz	Port 1	3 kHz	- 82	_____	N/A
300 kHz - 3 GHz	Port 1	10 Hz	- 102	_____	N/A
300 kHz - 3 GHz	Port 2	10 Hz	- 102	_____	N/A
300 kHz - 3 GHz	Port 2	3 kHz	- 82	_____	N/A

HP 8753D Performance Test Record (6 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____			
Serial Number _____	Date _____			
►► 7. Test Port Input Frequency Response				
Frequency Range	Test Port	Specification (dB)	Measured Value (dB)	Measurement Uncertainty (dB)
300 kHz—3 GHz	Port 2	± 1	_____	0.47
300 kHz—3 GHz	Port 1	± 1	_____	0.47
►► 8. Test Port Crosstalk				
Test Settings	Specification (dB)	Measured Value (dB)	Measurement Uncertainty	
Crosstalk to Test Port 2 300 kHz—3 GHz	< -100	_____	N/A	
Crosstalk to Test Port 1 300 kHz—3 GHz	< -100	_____	N/A	

HP 8753D Performance Test Record (7 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____			
Serial Number _____	Date _____			
► 9. Calibration Coefficients				
Test Description	Frequency Range	Spec. (dB)	Measured Value (dB)	Measurement Uncertainty (dB)
Forward Direction				
Directivity	300 kHz - 1.3 GHz	≥ 35	_____	± 0.9
Directivity	1.3 GHz - 3 GHz	≥ 30	_____	± 0.8
Forward Direction				
Source Match	300 kHz - 1.3 GHz	≥ 16	_____	± 0.2
Source Match	1.3 GHz - 3 GHz	≥ 16	_____	± 0.2
Forward Direction				
Trans. Tracking	300 kHz - 1.3 GHz	± 1.5	_____	± 0.006
Trans. Tracking	1.3 GHz - 3 GHz	± 1.5	_____	± 0.009
Forward Direction				
Refl. Tracking	300 kHz - 1.3 GHz	± 1.5	_____	± 0.001
Refl. Tracking	1.3 GHz - 3 GHz	± 1.5	_____	± 0.005
Reverse Direction				
Load Match	300 kHz - 1.3 GHz	≥ 18	_____	± 0.1
Load Match	1.3 GHz - 3 GHz	≥ 16	_____	± 0.2

HP 8753D Performance Test Record (8 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____			
Serial Number _____	Date _____			
► 9. Calibration Coefficients (continued)				
Test Description	Frequency Range	Spec. (dB)	Measured Value (dB)	Measurement Uncertainty (dB)
Reverse Direction				
Trans. Tracking	300 kHz - 1.3 GHz	± 1.5	_____	± 0.006
Trans. Tracking	1.3 GHz - 3 GHz	± 1.5	_____	± 0.009
Forward Direction				
Load Match	300 kHz - 1.3 GHz	≥ 18	_____	± 0.1
Load Match	1.3 GHz - 3 GHz	≥ 16	_____	± 0.2
Reverse Direction				
Directivity	300 kHz - 1.3 GHz	≥ 35	_____	± 0.9
Directivity	1.3 GHz - 3 GHz	≥ 30	_____	± 0.8
Reverse Direction				
Source Match	300 kHz - 1.3 GHz	≥ 16	_____	± 0.2
Source Match	1.3 GHz - 3 GHz	≥ 16	_____	± 0.2
Reverse Direction				
Refl. Tracking	300 kHz - 1.3 GHz	± 1.5	_____	± 0.001
Refl. Tracking	1.3 GHz - 3 GHz	± 1.5	_____	± 0.005

HP 8753D Performance Test Record (9 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____			
Serial Number _____	Date _____			
►► 10. System Trace Noise				
CW Frequency (GHz)	Ratio	Specification	Measured Value	Measurement Uncertainty
3	A/R	< 0.006 dB rms	_____	±0.001 dB
3	A/R	< 0.038° rms	_____	±0.01°
3	B/R	< 0.006 dB rms	_____	±0.001 dB
3	B/R	< 0.038° rms	_____	±0.01°
►► 12. Test Port Input Impedance				
Frequency Range	Test Port	Return Loss (dB)	Specification (dB)	Measurement Uncertainty (dB)
Frequency Range	Test Port	Return Loss (dB)	Specification (dB)	Measurement Uncertainty (dB)
30 kHz—300 kHz (Typical for Option 075)	Port 2	_____	≥ 14	± 1.5
50 kHz—300 kHz	Port 2	_____	≥ 20	± 1.5
300 kHz—1.3 GHz	Port 2	_____	≥ 18	± 1.5
1.3 GHz—3 GHz	Port 2	_____	≥ 16	± 1.5
30 kHz—300 kHz (Typical for Option 075)	Port 1	_____	≥ 14	± 1.5
50 kHz—300 kHz	Port 1	_____	≥ 20	± 1.5
300 kHz—1.3 GHz	Port 1	_____	≥ 18	± 1.5
1.3 GHz—3 GHz	Port 1	_____	≥ 16	± 1.5

HP 8753D Performance Test Record (10 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D			Report Number _____			
Serial Number _____			Date _____			
►► 13. Test Port Receiver Magnitude Dynamic Accuracy						
Test Port Input Power	8496A Attn. (dB)	G Test Port Measurement (dBm)	F Expected Measurement (corrected) (dBm)	G - F Dynamic Accuracy (Calculated)	Spec. (dB)	Meas. Uncer. (dB)
Test Port 2						
– 10	0	_____	_____	_____	≤ 0.059	± 0.006
– 20 (ref)	10	_____	_____	_____	≤ 0.050	Reference
– 30	20	_____	_____	_____	≤ 0.050	± 0.006
– 40	30	_____	_____	_____	≤ 0.053	± 0.006
– 50	40	_____	_____	_____	≤ 0.058	± 0.006
– 60	50	_____	_____	_____	≤ 0.095	± 0.015
– 70	60	_____	_____	_____	≤ 0.250	± 0.015
– 80	70	_____	_____	_____	≤ 0.750	± 0.015
– 90	80	_____	_____	_____	≤ 2.200	± 0.015
– 100	90	_____	_____	_____	< 5.200	± 0.025
Test Port 1						
– 10	0	_____	_____	_____	≤ 0.059	± 0.006
– 20 (ref)	10	_____	_____	_____	≤ 0.050	Reference
– 30	20	_____	_____	_____	≤ 0.050	± 0.006
– 40	30	_____	_____	_____	≤ 0.053	± 0.006
– 50	40	_____	_____	_____	≤ 0.058	± 0.006
– 60	50	_____	_____	_____	≤ 0.095	± 0.015
– 70	60	_____	_____	_____	≤ 0.250	± 0.015
– 80	70	_____	_____	_____	≤ 0.750	± 0.015
– 90	80	_____	_____	_____	≤ 2.200	± 0.015
– 100	90	_____	_____	_____	< 5.200	± 0.025

HP 8753D Performance Test Record (11 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D		Report Number _____				
Serial Number _____		Date _____				
►► 14. Test Port Receiver Phase Dynamic Accuracy						
Test Port Input Power	Calculated Value (dB)	A	B	Results Value (degrees)	Spec. (degrees)	Meas. Uncert.
Test Port 2						
- 10	_____	_____	_____	_____	≤ 0.42	N/A
- 20	_____	_____	_____	_____	≤ 0.35	N/A
- 30	_____	_____	_____	_____	≤ 0.35	N/A
- 40	_____	_____	_____	_____	≤ 0.36	N/A
- 50	_____	_____	_____	_____	≤ 0.39	N/A
- 60	_____	_____	_____	_____	≤ 0.64	N/A
- 70	_____	_____	_____	_____	≤ 1.75	N/A
- 80	_____	_____	_____	_____	≤ 5.00	N/A
- 90	_____	_____	_____	_____	≤ 17.50	N/A
- 100	_____	_____	_____	_____	≤ 53.00	N/A
Test Port 1						
- 10	_____	_____	_____	_____	≤ 0.42	N/A
- 20	_____	_____	_____	_____	≤ 0.35	N/A
- 30	_____	_____	_____	_____	≤ 0.35	N/A
- 40	_____	_____	_____	_____	≤ 0.36	N/A
- 50	_____	_____	_____	_____	≤ 0.39	N/A
- 60	_____	_____	_____	_____	≤ 0.64	N/A
- 70	_____	_____	_____	_____	≤ 1.75	N/A
- 80	_____	_____	_____	_____	≤ 5.00	N/A
- 90	_____	_____	_____	_____	≤ 17.50	N/A
- 100	_____	_____	_____	_____	≤ 53.00	N/A

HP 8753D Performance Test Record (12 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____			
Serial Number _____	Date _____			
►► 15. Test Port Receiver Magnitude Compression				
CW Frequency	Test Port	Measured Value (dB)	Specification (dB)	Measurement Uncertainty
50 MHz	Port 2	_____	≤ 0.45	N/A
1 GHz	Port 2	_____	≤ 0.45	N/A
2 GHz	Port 2	_____	≤ 0.45	N/A
3 GHz	Port 2	_____	≤ 0.45	N/A
50 MHz	Port 1	_____	≤ 0.45	N/A
1 GHz	Port 1	_____	≤ 0.45	N/A
2 GHz	Port 1	_____	≤ 0.45	N/A
3 GHz	Port 1	_____	≤ 0.45	N/A
►► 16. Test Port Receiver Phase Compression				
CW Frequency	Test Port	Measured Value (degrees)	Specification (degrees)	Measurement Uncertainty
50 MHz	Port 2	_____	≤ 6°	N/A
1 GHz	Port 2	_____	≤ 6°	N/A
2 GHz	Port 2	_____	≤ 6°	N/A
3 GHz	Port 2	_____	≤ 6°	N/A
50 MHz	Port 1	_____	≤ 6°	N/A
1 GHz	Port 1	_____	≤ 6°	N/A
2 GHz	Port 1	_____	≤ 6°	N/A
3 GHz	Port 1	_____	≤ 6°	N/A

HP 8753D Performance Test Record (13 of 13)
For 30 kHz—3 GHz Analyzers

Hewlett-Packard Company Model HP 8753D	Report Number _____		
Serial Number _____	Date _____		
►► 17. Test Port Output/Input Harmonics (Option 002 without Option 006)			
Test Description	Specification (dBc)	Measurement Value (dBc)	Measurement Uncertainty (dB)
Test Port Output Harmonics			
2nd	≤ 25	_____	± 1.0
3rd	≤ 25	_____	± 1.0
Port 1 Input Harmonics			
2nd	≤ 15	_____	± 1.0
3rd	≤ 30	_____	± 1.0
Port 2 Input Harmonics			
2nd	≤ 15	_____	± 1.0
3rd	≤ 30	_____	± 1.0

2b

Performance Test Record

**For Analyzers with a Frequency Range of
30 kHz to 6 GHz**

Note See the previous “Performance Test Record” section if your analyzer frequency range is from 30 kHz to 3 GHz.

HP 8753D Performance Test Record (1 of 15)

Calibration Lab Address:	Report Number _____
	Date _____
	Last Calibration Date _____
	Customer's Name _____
	Performed by _____

Model HP 8753D Option 006

Serial No. _____ Option(s) _____
Firmware Revision _____
Ambient Temperature _____ °C Relative Humidity _____ %

Test Equipment Used:

Description	Model Number	Trace Number	Cal Due Date
-------------	--------------	--------------	--------------

Frequency Counter	_____	_____	_____
-------------------	-------	-------	-------

Power Meter	_____	_____	_____
-------------	-------	-------	-------

Power Sensor	_____	_____	_____
--------------	-------	-------	-------

Calibration Kit	_____	_____	_____
-----------------	-------	-------	-------

Verification Kit	_____	_____	_____
------------------	-------	-------	-------

Notes/Comments: _____

HP 8753D Performance Test Record (2 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
►► 1. Test Port Output Frequency Range and Accuracy				
Test Frequencies (MHz)	Min. (MHz)	Results Measured (MHz)	Max. (MHz)	Measurement Uncertainty (MHz)
0.03	0.029 999 7	_____	0.030 000 3	± 0.000 000 050
0.3	0.299 997	_____	0.300 003	± 0.000 000 520
5.0	4.999 950	_____	5.000 050	± 0.000 009
16.0	15.999 840	_____	16.000 160	± 0.000 028
31.0	30.999 690	_____	31.000 310	± 0.000 054
60.999 999	60.999 390	_____	61.000 610	± 0.000 105
121.0	120.998 790	_____	121.001 210	± 0.000 207
180.0	179.998 200	_____	180.001 800	± 0.000 307
310.0	309.995 900	_____	310.003 100	± 0.000 528
700.0	699.930 000	_____	700.007 000	± 0.001 192
1 300.0	1 299.987	_____	1 300.013	± 0.002 212
2 000.0	1 999.980	_____	2 000.020	± 0.003 403
3 000.0	2 999.970	_____	3 000.030	± 0.005 104
4.0	3.999 960	_____	4.000 040	± 0.006 805
5.0	4.999 950	_____	5.000 050	± 0.008 506
6.0	5.999 940	_____	6.000 060	± 0.010 207

HP 8753D Performance Test Record (3 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
►► 2. External Source Mode Frequency Range				
Test Frequencies (GHz)	Result			
0.010	_____			
0.020	_____			
0.100	_____			
1.000	_____			
2.000	_____			
3.000	_____			
4.000	_____			
5.000	_____			
6.000	_____			
►► 3. Test Port Output Power Accuracy				
Test Frequency	Test Port Output Power (dBm)	Specification (dB)	Measured Value (dB)	Measurement Uncertainty (dB)
300 kHz	0	± 1	_____	± 0.47
20 MHz	0	± 1	_____	± 0.25
50 MHz	0	± 1	_____	± 0.12
100 MHz	0	± 1	_____	± 0.12
200 MHz	0	± 1	_____	± 0.12
500 MHz	0	± 1	_____	± 0.12
1 GHz	0	± 1	_____	± 0.12
2 GHz	0	± 1	_____	± 0.15
3 GHz	0	± 1	_____	± 0.15
4 GHz	0	± 1	_____	± 0.17
5 GHz	0	± 1	_____	± 0.17
6 GHz	0	± 1	_____	± 0.17

2b-4 Performance Test Record

HP 8753D Performance Test Record (4 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
► 4. Test Port Output Power Range and Linearity				
Test Settings	Results Measured (dB)	Power Level Linearity (dB)	Specification (dB)	Meas. Uncert. (dB)
CW Frequency = 300 kHz				
- 15	_____	_____	± 0.2	± 0.03
- 13	_____	_____	± 0.2	± 0.03
- 11	_____	_____	± 0.2	± 0.03
- 9	_____	_____	± 0.2	± 0.02
- 7	_____	_____	± 0.2	± 0.02
- 5	_____	_____	± 0.2	± 0.02
- 3	_____	_____	± 0.2	± 0.02
- 1	_____	_____	± 0.2	± 0.02
+ 1	_____	_____	± 0.2	± 0.03
+ 3	_____	_____	± 0.2	± 0.03
+ 5	_____	_____	± 0.5	± 0.03
+ 7	_____	_____	± 0.5	± 0.03
+ 9	_____	_____	± 0.5	± 0.03
+ 10	_____	_____	± 0.5	± 0.03
CW Frequency = 3 GHz				
- 15	_____	_____	± 0.2	± 0.03
- 13	_____	_____	± 0.2	± 0.03
- 11	_____	_____	± 0.2	± 0.03
- 9	_____	_____	± 0.2	± 0.02
- 7	_____	_____	± 0.2	± 0.02
- 5	_____	_____	± 0.2	± 0.02
- 3	_____	_____	± 0.2	± 0.02
- 1	_____	_____	± 0.2	± 0.02
+ 1	_____	_____	± 0.2	± 0.03
+ 3	_____	_____	± 0.2	± 0.03
+ 5	_____	_____	± 0.5	± 0.03

HP 8753D Performance Test Record (5 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
►► 4. Test Port Output Power Range and Linearity (continued)				
Test Settings	Results Measured (dB)	Power Level Linearity (dB)	Specification (dB)	Meas. Uncert. (dB)
+ 7	_____	_____	± 0.5	± 0.03
+ 9	_____	_____	± 0.5	± 0.03
+ 10	_____	_____	± 0.5	± 0.03
CW Frequency = 6 GHz				
- 15	_____	_____	± 0.2	± 0.03
- 13	_____	_____	± 0.2	± 0.03
- 11	_____	_____	± 0.2	± 0.03
- 9	_____	_____	± 0.2	± 0.03
- 7	_____	_____	± 0.2	± 0.02
- 5	_____	_____	± 0.2	± 0.02
- 3	_____	_____	± 0.2	± 0.02
- 1	_____	_____	± 0.2	± 0.02
+ 1	_____	_____	± 0.2	± 0.02
+ 3	_____	_____	± 0.2	± 0.03
+ 5	_____	_____	± 0.5	± 0.03
+ 7	_____	_____	± 0.5	± 0.03
+ 9	_____	_____	± 0.5	± 0.03
+ 10	_____	_____	± 0.5	± 0.03

HP 8753D Performance Test Record (6 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006		Report Number _____			
Serial Number _____		Date _____			
►► 5. Minimum R Channel Level					
CW Frequency	Specification (dB)	Test Port Power	Measurement Uncertainty (dB)		
300 kHz	< -35	_____	± 1.0		
3.29 MHz	< -35	_____	± 1.0		
3.31 MHz	< -35	_____	± 1.0		
15.90 MHz	< -35	_____	± 1.0		
16.10 MHz	< -35	_____	± 1.0		
30.90 MHz	< -35	_____	± 1.0		
31.10 MHz	< -35	_____	± 1.0		
1.6069 GHz	< -35	_____	± 1.0		
1.6071 GHz	< -35	_____	± 1.0		
3.000 GHz	< -35	_____	± 2.0		
4.000 GHz	< -30	_____	± 2.0		
5.000 GHz	< -30	_____	± 2.0		
6.000 GHz	< -30	_____	± 2.0		
►► 6. Test Port Input Noise Floor Level					
Frequency Range	Test Port	IF Bandwidth	Specification (dBm)	Calculated Value	Measurement Uncertainty
300 kHz—3 GHz	Port 1	3 kHz	- 82	_____	N/A
300 kHz—3 GHz	Port 1	10 Hz	- 102	_____	N/A
300 kHz—3 GHz	Port 2	10 Hz	- 102	_____	N/A
300 kHz—3 GHz	Port 2	3 kHz	- 82	_____	N/A
3 GHz—6 GHz	Port 2	3 kHz	- 77	_____	N/A
3 GHz—6 GHz	Port 2	10 Hz	- 97	_____	N/A
3 GHz—6 GHz	Port 1	10 Hz	- 97	_____	N/A
3 GHz—6 GHz	Port 1	3 kHz	- 77	_____	N/A

HP 8753D Performance Test Record (7 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____		
Serial Number _____	Date _____		
►► 7. Test Port Input Frequency Response			
Frequency Range	Test Port	Specification (dB)	Measured Value (dB)
300 kHz—3 GHz	Port 2	± 1	_____
300 kHz—3 GHz	Port 1	± 1	_____
3 GHz—6 GHz	Port 1	± 2	_____
3 GHz—6 GHz	Port 2	± 2	_____
►► 8. Test Port Crosstalk			
Test Settings	Specification (dB)	Measured Value (dB)	Measurement Uncertainty
Crosstalk to Test Port 2 300 kHz—3 GHz	< -100	_____	N/A
Crosstalk to Test Port 1 300 kHz—3 GHz	< -100	_____	N/A
Crosstalk to Test Port 1 3 GHz—6 GHz	< -90	_____	N/A
Crosstalk to Test Port 2 3 GHz—6 GHz	< -90	_____	N/A

HP 8753D Performance Test Record (8 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
►► 9. Calibration Coefficients				
Test Description	Frequency Range	Spec. (dB)	Measured Value (dB)	Measurement Uncertainty (dB)
Forward Direction				
Directivity	300 kHz—1.3 GHz	≥ 35	_____	± 0.9
Directivity	1.3 GHz—3 GHz	≥ 30	_____	± 0.8
Directivity	3 GHz—6 GHz	≥ 25	_____	± 0.8
Forward Direction				
Source Match	300 kHz—1.3 GHz	≥ 16	_____	± 0.2
Source Match	1.3 GHz—3 GHz	≥ 16	_____	± 0.2
Source Match	3 GHz—6 GHz	≥ 14	_____	± 0.3
Forward Direction				
Trans. Tracking	300 kHz—1.3 GHz	± 1.5	_____	± 0.006
Trans. Tracking	1.3 GHz—3 GHz	± 1.5	_____	± 0.009
Trans. Tracking	3 GHz—6 GHz	± 2.5	_____	± 0.021
Forward Direction				
Refl. Tracking	300 kHz—1.3 GHz	± 1.5	_____	± 0.001
Refl. Tracking	1.3 GHz—3 GHz	± 1.5	_____	± 0.005
Refl. Tracking	3 GHz—6 GHz	± 2.5	_____	± 0.020
Reverse Direction				
Load Match	300 kHz—1.3 GHz	≥ 18	_____	± 0.1
Load Match	1.3 GHz—3 GHz	≥ 16	_____	± 0.2
Load Match	3 GHz—6 GHz	≥ 14	_____	± 0.2

HP 8753D Performance Test Record (9 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
► 9. Calibration Coefficients (continued)				
Test Description	Frequency Range	Spec. (dB)	Measured Value (dB)	Measurement Uncertainty (dB)
Reverse Direction				
Trans. Tracking	300 kHz—1.3 GHz	± 1.5	_____	± 0.006
Trans. Tracking	1.3 GHz—3 GHz	± 1.5	_____	± 0.009
Trans. Tracking	3 GHz—6 GHz	± 2.5	_____	± 0.021
Forward Direction				
Load Match	300 kHz—1.3 GHz	≥ 18	_____	± 0.1
Load Match	1.3 GHz—3 GHz	≥ 16	_____	± 0.2
Load Match	3 GHz—6 GHz	≥ 14	_____	± 0.2
Reverse Direction				
Directivity	300 kHz—1.3 GHz	≥ 35	_____	± 0.9
Directivity	1.3 GHz—3 GHz	≥ 30	_____	± 0.8
Directivity	3 GHz—6 GHz	≥ 25	_____	± 0.8
Reverse Direction				
Source Match	300 kHz - 1.3 GHz	≥ 16	_____	± 0.2
Source Match	1.3 GHz - 3 GHz	≥ 16	_____	± 0.2
Source Match	3 GHz - 6 GHz	≥ 14	_____	± 0.3
Reverse Direction				
Refl. Tracking	300 kHz - 1.3 GHz	± 1.5	_____	± 0.001
Refl. Tracking	1.3 GHz - 3 GHz	± 1.5	_____	± 0.005
Refl. Tracking	3 GHz - 6 GHz	± 2.5	_____	± 0.020

2b-10 Performance Test Record

HP 8753D Performance Test Record (10 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
►► 11. System Trace Noise				
Frequency (GHz)	Ratio	Measured Value	Specification	Measurement Uncertainty
3	A/R (Magnitude)	_____	≤ 0.006 dB rms	± 0.001 dB
6	A/R (Magnitude)	_____	≤ 0.010 dB rms	± 0.001 dB
6	A/R (Phase)	_____	≤ 0.070° rms	± 0.01 °
3	A/R (Phase)	_____	≤ 0.038° rms	± 0.01 °
3	B/R (Magnitude)	_____	≤ 0.006 dB rms	± 0.001 dB
6	B/R (Magnitude)	_____	≤ 0.010 dB rms	± 0.001 dB
6	B/R (Phase)	_____	≤ 0.070° rms	± 0.01 °
3	B/R (Phase)	_____	≤ 0.038° rms	± 0.01 °
►► 12. Test Port Input Impedance				
Test Description	Test Port	Return Loss (dB)	Specification (dB)	Measurement Uncertainty (dB)
30 kHz—300 kHz (Typical for Option 075)	Port 2	_____	≥ 14	± 1.5
50 kHz—300 kHz	Port 2	_____	≥ 20	± 1.5
300 kHz—1.3 GHz	Port 2	_____	≥ 18	± 1.5
1.3 GHz—3 GHz	Port 2	_____	≥ 16	± 1.5
3 GHz—6 GHz	Port 2	_____	≥ 14	± 1.0
30 kHz—300 kHz (Typical for Option 075)	Port 1	_____	≥ 14	± 1.5
50 kHz—300 kHz	Port 1	_____	≥ 20	± 1.5
300 kHz—1.3 GHz	Port 1	_____	≥ 18	± 1.5
1.3 GHz—3 GHz	Port 1	_____	≥ 16	± 1.5
3 GHz—6 GHz	Port 1	_____	≥ 14	± 1.0

HP 8753D Performance Test Record (11 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006			Report Number _____			
Serial Number _____			Date _____			
►► 13. Test Port Receiver Magnitude Dynamic Accuracy						
Test Port Input Power	8496A Attn. (dB)	G Test Port Measurement (dBm)	F Expected Measurement (corrected) (dBm)	G - F Dynamic Accuracy (Calculated)	Spec. (dB)	Meas. Uncer. (dB)
Test Port 2						
– 10	0	_____	_____	_____	≤ 0.059	± 0.006
– 20 (ref)	10	_____	_____	_____	≤ 0.050	Reference
– 30	20	_____	_____	_____	≤ 0.050	± 0.006
– 40	30	_____	_____	_____	≤ 0.053	± 0.006
– 50	40	_____	_____	_____	≤ 0.058	± 0.006
– 60	50	_____	_____	_____	≤ 0.095	± 0.015
– 70	60	_____	_____	_____	≤ 0.250	± 0.015
– 80	70	_____	_____	_____	≤ 0.750	± 0.015
– 90	80	_____	_____	_____	≤ 2.200	± 0.015
– 100	90	_____	_____	_____	< 5.200	± 0.025
Test Port 1						
– 10	0	_____	_____	_____	≤ 0.059	± 0.006
– 20 (ref)	10	_____	_____	_____	≤ 0.050	Reference
– 30	20	_____	_____	_____	≤ 0.050	± 0.006
– 40	30	_____	_____	_____	≤ 0.053	± 0.006
– 50	40	_____	_____	_____	≤ 0.058	± 0.006
– 60	50	_____	_____	_____	≤ 0.095	± 0.015
– 70	60	_____	_____	_____	≤ 0.250	± 0.015
– 80	70	_____	_____	_____	≤ 0.750	± 0.015
– 90	80	_____	_____	_____	≤ 2.200	± 0.015
– 100	90	_____	_____	_____	< 5.200	± 0.025

2b-12 Performance Test Record

HP 8753D Performance Test Record (12 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006		Report Number _____				
Serial Number _____		Date _____				
►► 14. Test Port Receiver Phase Dynamic Accuracy						
Test Port Input Power	Calculated Value (dB)	A	B	Results Value (degrees)	Spec. (degrees)	Meas. Uncert.
Test Port 2						
– 10	_____	_____	_____	_____	≤ 0.42	± 0.04°
– 20	_____	_____	_____	_____	≤ 0.35	Ref.
– 30	_____	_____	_____	_____	≤ 0.35	± 0.04°
– 40	_____	_____	_____	_____	≤ 0.36	± 0.04°
– 50	_____	_____	_____	_____	≤ 0.39	± 0.04°
– 60	_____	_____	_____	_____	≤ 0.64	± 0.10°
– 70	_____	_____	_____	_____	≤ 1.75	± 0.10°
– 80	_____	_____	_____	_____	≤ 5.00	± 0.10°
– 90	_____	_____	_____	_____	≤ 17.50	± 0.10°
– 100	_____	_____	_____	_____	≤ 53.00	± 0.20°
Test Port 1						
– 10	_____	_____	_____	_____	≤ 0.42	± 0.04°
– 20	_____	_____	_____	_____	≤ 0.35	Ref.
– 30	_____	_____	_____	_____	≤ 0.35	± 0.04°
– 40	_____	_____	_____	_____	≤ 0.36	± 0.04°
– 50	_____	_____	_____	_____	≤ 0.39	± 0.10°
– 60	_____	_____	_____	_____	≤ 0.64	± 0.10°
– 70	_____	_____	_____	_____	≤ 1.75	± 0.10°
– 80	_____	_____	_____	_____	≤ 5.00	± 0.10°
– 90	_____	_____	_____	_____	≤ 17.50	± 0.10°
– 100	_____	_____	_____	_____	≤ 53.00	± 0.20°

HP 8753D Performance Test Record (13 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
►► 15. Test Port Receiver Magnitude Compression				
CW Frequency	Test Port	Measured Value (dB)	Specification (dB)	Measurement Uncertainty
50 MHz	Port 2	_____	≤ 0.45	N/A
1 GHz	Port 2	_____	≤ 0.45	N/A
2 GHz	Port 2	_____	≤ 0.45	N/A
3 GHz	Port 2	_____	≤ 0.45	N/A
4 GHz	Port 2	_____	≤ 0.80	N/A
5 GHz	Port 2	_____	≤ 0.80	N/A
6 GHz	Port 2	_____	≤ 0.80	N/A
50 MHz	Port 1	_____	≤ 0.45	N/A
1 GHz	Port 1	_____	≤ 0.45	N/A
2 GHz	Port 1	_____	≤ 0.45	N/A
3 GHz	Port 1	_____	≤ 0.45	N/A
4 GHz	Port 1	_____	≤ 0.80	N/A
5 GHz	Port 1	_____	≤ 0.80	N/A
6 GHz	Port 1	_____	≤ 0.80	N/A

HP 8753D Performance Test Record (14 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____			
Serial Number _____	Date _____			
►► 16. Test Port Receiver Phase Compression				
CW Frequency	Test Port	Measured Value (degrees)	Specification (degrees)	Measurement Uncertainty
50 MHz	Port 2	_____	≤ 6	N/A
1 GHz	Port 2	_____	≤ 6	N/A
2 GHz	Port 2	_____	≤ 6	N/A
3 GHz	Port 2	_____	≤ 6	N/A
4 GHz	Port 2	_____	≤ 7.5	N/A
5 GHz	Port 2	_____	≤ 7.5	N/A
6 GHz	Port 2	_____	≤ 7.5	N/A
50 MHz	Port 1	_____	≤ 6	N/A
1 GHz	Port 1	_____	≤ 6	N/A
2 GHz	Port 1	_____	≤ 6	N/A
3 GHz	Port 1	_____	≤ 6	N/A
4 GHz	Port 1	_____	≤ 7.5	N/A
5 GHz	Port 1	_____	≤ 7.5	N/A
6 GHz	Port 1	_____	≤ 7.5	N/A

HP 8753D Performance Test Record (15 of 15)
For 30 kHz—6 GHz Analyzers

Hewlett-Packard Company Model HP 8753D Option 006	Report Number _____		
Serial Number _____	Date _____		
►► 18. Output/Input Test Port Harmonics (Option 002 only)			
Test Description	Specification (dBc)	Measurement Value (dBc)	Measurement Uncertainty (dB)
Test Port Output Harmonics			
2nd	≤ 25	_____	± 1.0
3rd	≤ 25	_____	± 1.0
Port 1 Input Harmonics			
2nd	≤ 15	_____	± 1.0
3rd	≤ 30	_____	± 1.0
Port 2 Input Harmonics			
2nd	≤ 15	_____	± 1.0
3rd	≤ 30	_____	± 1.0

3

Adjustments and Correction Constants

This chapter has the following adjustment procedures:

- A9 CC Jumper Positions
- Source Default Correction Constants (Test 44)
- Source Pretune Default Correction Constants (Test 45)
- Analog Bus Correction Constants (Test 46)
- RF Output Power Correction Constants (Test 47)
- Source Pretune Correction Constants (Test 48)
- Display Intensity Adjustments (Test 49)
- IF Amplifier Correction Constants (Test 51)
- ADC Offset Correction Constants (Test 52)
- Sampler Magnitude and Phase Correction Constants (Test 53)
- Cavity Oscillator Frequency Correction Constants (Test 54)
- Serial Number Correction Constants (Test 55)
- Option Numbers Correction Constants (Test 56)
- Calibration Kit Default Correction Constants (Test 57)
- Initialize EEPROMs (Test 58)
- EEPROM Backup Disk Procedure
- Vertical Position and Focus Adjustments
- Display Degaussing (Demagnetizing)
- Fractional-N Frequency Range Adjustment
- Frequency Accuracy Adjustment
- High/Low Band Transition Adjustment
- Fractional-N Spur Avoidance and FM Sideband Adjustment
- Source Spur Avoidance Tracking Adjustment
- Unprotected Hardware Option Numbers Correction Constants

Post-Repair Procedures for HP 8753D

Table 3-1 lists the additional service procedures which you must perform to ensure that the instrument is working correctly, following the replacement of an assembly.

Perform the procedures in the order that they are listed in the table.

3-2 Adjustments and Correction Constants

Table 3-1. Related Service Procedures

Replaced Assembly	Adjustments/ Correction Constants (CC)	Verification
A1 Front Panel Keyboard	None	Internal Test 0 Internal Test 23
A2 Front Panel Interface	None	Internal Test 0 Internal Test 23 Internal Test 12
A3 Source	A9 CC Jumper Positions Source Def CC (Test 44) Pretune Default CC (Test 45) Analog Bus CC (Test 46) Source Pretune CC (Test 48) RF Output Power CC (Test 47) Sampler Magnitude and Phase CC (Test 53) Cavity Oscillator Frequency CC (Test 54) Source Spur Avoidance Tracking EEPROM Backup Disk	Output Power Spectral Purity (harmonics and mixer spurs) or System Verification
A4/A5/A6 Samplers	A9 CC Jumper Positions Sampler Magnitude and Phase CC (Test 53) IF Amplifier CC (Test 51) EEPROM Backup Disk	Minimum R Level (if R sampler replaced) Input Crosstalk Absolute Amplitude Accuracy Frequency Response or System Verification
A7 Pulse Generator	A9 CC Jumper Positions Sampler Magnitude and Phase CC (Test 53) EEPROM Backup Disk	Frequency Response Frequency Range and Accuracy Spectral Purity (phase noise) or System Verification
A8 Post Regulator	A9 CC Jumper Positions Cavity Oscillator Frequency CC (Test 54) Source Spur Avoidance Tracking EEPROM Backup Disk	Internal Test 0 Check A8 test point voltages

Table 3-1. Related Service Procedures (2 of 3)

Replaced Assembly	Adjustments/ Correction Constants (CC)	Verification
A9 CPU ¹	A9 CC Jumper Positions Serial Number CC (Test 55) Option Number CC (Test 56) Display Intensity and Focus CC (Test 49) Source Def CC (Test 44) Pretune Default CC (Test 45) Analog Bus CC (Test 46) Cal Kit Default (Test 57) Source Pretune CC (Test 48) RF Output Power CC (Test 47) Sampler Magnitude and Phase CC (Test 53) ADC Linearity CC (Test 52) IF Amplifier CC (Test 51) Cavity Oscillator Frequency CC (Test 54) EEPROM Backup Disk	Output Power Absolute Amplitude Accuracy Frequency Response Dynamic Accuracy or System Verification
Firmware Rev 5.20 08753-60185	A9 CC Jumper Positions Source Default CC (Test 44) Pretune Default CC (Test 45) Analog Bus CC (Test 46) RF Output Power Correction Constants (Test 47) Source Pretune CC (Test 48) Sampler Magnitude and Phase CC (Test 53) EEPROM Backup Disk	Internal Test 0
A10 Digital IF	A9 CC Jumper Positions Analog Bus CC (Test 46) Sampler Magnitude and Phase CC (Test 53) ADC Linearity CC (Test 52) IF Amplifier CC (Test 51) EEPROM Backup Disk	Receiver Noise Level Trace Noise Input Crosstalk Absolute Amplitude Accuracy or System Verification
A11 Phase Lock	A9 CC Jumper Positions Analog Bus CC (Test 46) Pretune Default CC (Test 45) Source Pretune CC (Test 48) EEPROM Backup Disk	Minimum R Level Frequency Accuracy or System Verification

1 If you have an EEPROM backup disk available, you only need to perform the first three tests listed.

3-4 Adjustments and Correction Constants

Table 3-1. Related Service Procedures (3 of 3)

Replaced Assembly	Adjustments/ Correction Constants (CC)	Verification
A12 Reference	A9 CC Jumper Positions High/Low Band Transition Frequency Accuracy EEPROM Backup Disk	Frequency Range and Accuracy
A13 Fractional-N (Analog)	A9 CC Jumper Positions Fractional-N Spur and FM Sideband EEPROM Backup Disk	Spectral Purity (other spurious signals) Frequency Range and Accuracy
A14 Fractional-N (Digital)	A9 CC Jumper Positions Fractional-N Frequency Range Fractional-N Spur Avoidance and FM Sideband EEPROM Backup Disk	Frequency Range and Accuracy or System Verification
A15 Preregulator	None	Self-Test
A16 Rear Panel Interface	None	Internal Test 13, Rear Panel
A17 Motherboard	None	Self-Test
A18 Display	Vertical Position and Focus Display Intensity (Test 49) (only if needed)	Observation of Display Tests 66 - 80
A19 Graphics System Processor	None	Observation of Display Tests 59 - 80

A9 CC Jumper Positions

1. Remove the power line cord from the analyzer.
2. Set the analyzer on its side.
3. Remove the two corner bumpers from the bottom of the instrument with the T-10 TORX screwdriver.
4. Loosen the captive screw on the bottom cover's back edge, with the T-15 TORX screwdriver.
5. Slide the cover toward the rear of the instrument.
6. Move the jumper, as shown in Figure 3-1.
 - Move the A9 CC jumper to the ALT position, before you run any of the correction constant adjustment routines. This is the position for altering the analyzer's correction constants.
 - Move the A9 CC jumper to the NRM position, after you have run correction constant adjustment routines. This is the position for normal operating conditions.
7. Reconnect the power line cord and switch on the instrument.

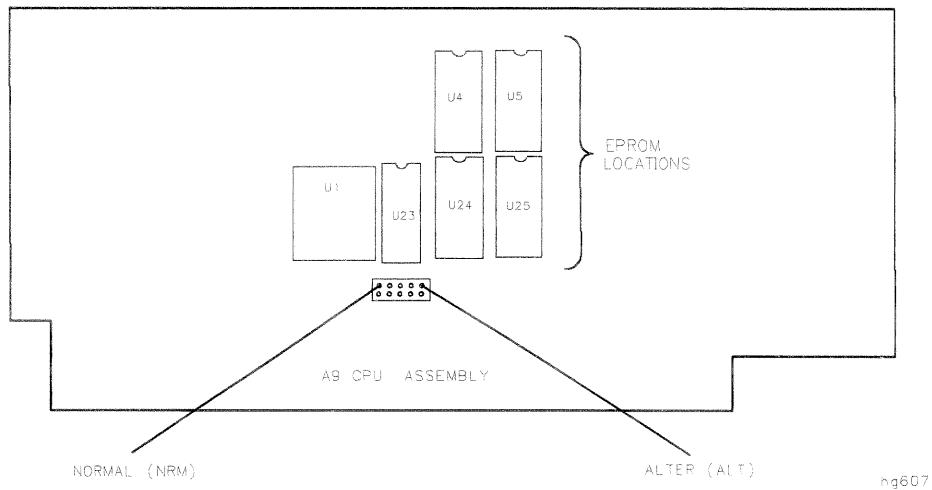


Figure 3-1. Partial Component Location Diagram

3-6 Adjustments and Correction Constants

Source Default Correction Constants (Test 44)

Analyzer warm-up time: 30 minutes.

This internal adjustment routine writes default correction constants for the source power accuracy.

1. Press **PRESET** **SYSTEM** SERVICE MENU TESTS **44** **x1** EXECUTE TEST YES .
2. Observe the analyzer for the results of the adjustment routine:
 - If the analyzer displays *Source Def DONE, you have completed this procedure.
 - If the analyzer displays *Source Def FAIL, refer to the “Source Troubleshooting” chapter.

Source Pretune Default Correction Constants (Test 45)

Analyzer warm-up time: 30 minutes.

This adjustment writes default correction constants for rudimentary phase lock pretuning accuracy.

1. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [45] [x1] EXECUTE TEST YES .
2. Observe the analyzer for the results of this adjustment routine:
 - If the analyzer displays Pretune Def DONE, you have completed this procedure.
 - If the analyzer displays FAIL, refer to “Source Troubleshooting.”

Analog Bus Correction Constants (Test 46)

Analyzer warm-up time: 30 minutes.

This procedure calibrates the analog bus by using three reference voltages (ground, +0.37 and +2.5 volts), then stores the calibration data as correction constants in EEPROMs.

1. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [46] [x1] EXECUTE TEST YES .
2. Observe the analyzer for the results of the adjustment routine:
 - If the analyzer displays ABUS Cor DONE, you have completed this procedure.
 - If the analyzer displays ABUS Cor FAIL, refer to the “Digital Control Troubleshooting” chapter.

RF Output Power Correction Constants (Test 47)

Required Equipment and Tools

Power Meter	HP 437B or HP 438A
HP-IB Cable	HP 10833A
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Additional Required Equipment for 50Ω Analyzers

Power Sensor	HP 8482A
Power Sensor (for Option 006 analyzers)	HP 8481A
Adapter APC-7 to Type-N (f)	HP 11524A

Additional Required Equipment for 75Ω Analyzers

Power Sensor	HP 8483A Option H03
--------------------	---------------------

Analyzer warm-up Time: 30 minutes.

This procedure adjusts several correction constants that can improve the output power level accuracy of the internal source. They are related to the power level, power slope, power slope offset, and the ALC roll-off factors among others.

1. If you just completed "Sampler Magnitude and Phase Correction Constants (Test 53)," continue this procedure with step 8.
2. Press [PRESET] [LOCAL] SYSTEM CONTROLLER .
3. Press [LOCAL] SET ADDRESSES ADDRESS: P MTR/HPIB . The default power meter address is 13. Refer to the power meter manual as required to observe or change its HP-IB address.
4. Press POWER MTR:438A/437 to toggle between the 438A/437 and 436A power meters. Choose the appropriate model number.

Note

If you are using the HP 438A power meter, connect the HP 8482A power sensor to channel A, and the HP 8481A power sensor to channel B.

3.10 Adjustments and Correction Constants

Power Sensor Calibration Factor Entry

5. Press **SYSTEM SERVICE MENU TEST OPTIONS LOSS/SENSR LISTS**
CAL FACTOR SENSOR A to access the calibration factor menu for power sensor A (HP 8482A for a 50Ω analyzer, or HP 8483A Option H03 for a 75Ω analyzer).
6. Zero and calibrate the power meter and power sensor. Refer to the power meter operating and service manual for more information on how to do this task.
7. Build a table of up to 12 points (12 frequencies with their calibration factors). To enter each point, follow these steps:
 - a. Press **ADD FREQUENCY**.
 - b. Input a frequency value and then press the appropriate key (**G/n**, **M/ μ** , or **k/m**).
 - c. Press **CAL FACTOR** and enter the calibration factor percentage that corresponds to the frequency you entered.
The cal factor and frequency values are found on the back of the sensor. If you make a mistake, press **⬅** and re-enter the correct value.
 - d. Press **DONE** to complete the data entry for each point.

Note

The following terms are part of the sensor calibration menu:

SEGMENT	allows you to select a frequency point.
EDIT	allows you to edit or change a previously entered value.
DELETE	allows you to delete a point from the sensor cal factor table.
ADD	allows you to add a point into the sensor cal factor table.
CLEAR LIST	allows you to erase the entire sensor cal factor table.
DONE	allows you to complete the points entry of the sensor cal factor table.

8. **For Option 006 Instruments Only:** Press CAL FACTOR SENSOR B to create a power sensor calibration table for power sensor B (HP 8481A), using the softkeys mentioned above.
9. Connect the equipment as shown in Figure 3-2.

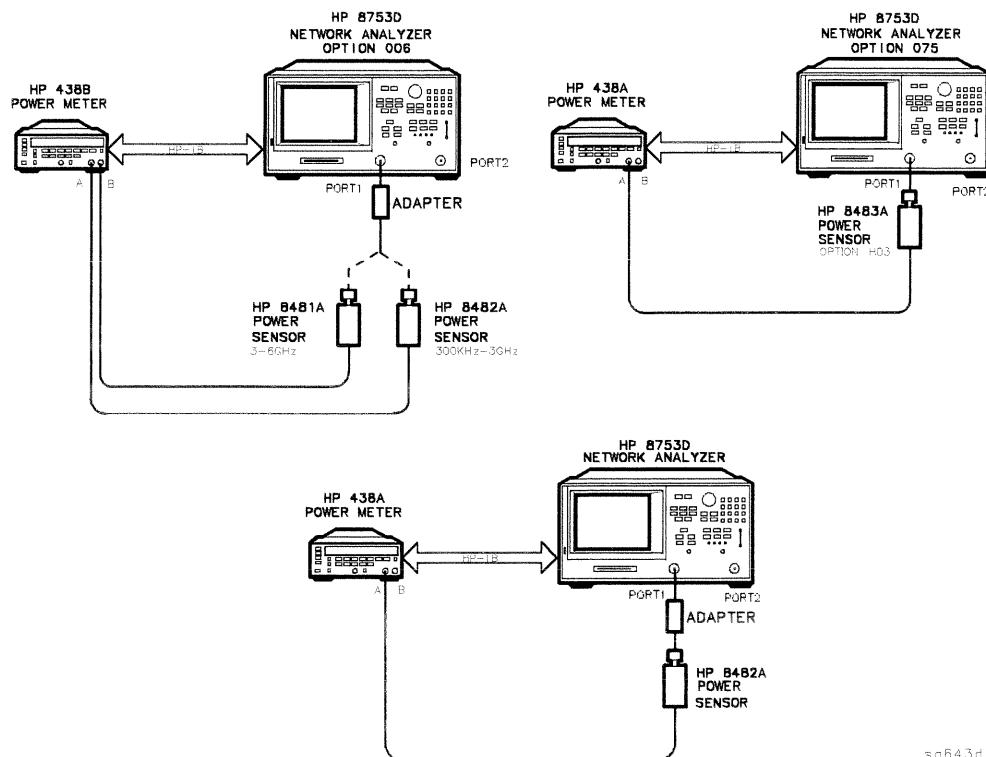


Figure 3-2. RF Output Correction Constants Test Setup for the HP 8753D

3-12 Adjustments and Correction Constants

10. Press **SYSTEM** SERVICE MENU TESTS **47** **x1**.
11. Press **EXECUTE TEST** and **YES** at the prompt to alter the correction constants.
12. Follow the instructions at the prompts and press **CONTINUE**.
13. When the analyzer completes the test, observe the display for the results:
 - If you see **DONE**, press **PRESET** and you have completed this procedure.
 - If you see **FAIL**, re-run this routine in the following order:
 - a. Press **PRESET**.
 - b. Repeat the “Source Default Correction Constants (Test 44)” procedure.
 - c. Repeat the “RF Output Power Correction Constants (Test 47)” procedure.

Source Pretune Correction Constants (Test 48)

Analyzer warm-up time: 30 minutes.

This procedure generates pretune values for correct phase-locked loop operation.

1. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [48] [x1] EXECUTE TEST YES .
2. Observe the analyzer for the results of this adjustment routine:
 - If the analyzer displays Pretune Cor DONE, you have completed this procedure.
 - If the analyzer displays FAIL, refer to “Source Troubleshooting.”

Display Intensity Adjustments (Test 49)

Required Equipment and Tools

Photometer	Tektronix J16 Photometer
Probe	Tektronix J6503
Light Occluder	Tektronix 016-0305-00
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Analyzer warm-up time: 30 minutes.

There are three display intensity adjustments:

- background
- maximum
- operating default

If either the A19 GSP, A9 CPU or A18 display assemblies are replaced, perform a visual inspection of the display. If it appears to need an adjustment, then proceed with the following procedures.

Note This procedure should be performed with a photometer and only by a qualified personnel.

Background Adjustment

1. In a dimly lit room (or with the analyzer display shaded from bright lights), press **PRESET** **SYSTEM** SERVICE MENU TESTS **49** **x1**.
2. The display should show **Intensity Cor - ND -**

Note The display could be so far out of adjustment that the annotation will be very difficult to read.

3. Press **EXECUTE TEST** and **YES** at the prompt to alter the correction constants. Alternating vertical bars of three different intensities will be drawn on the display. Each bar has a number written below it (either 0, 1, or 2).
4. Adjust the analyzer front panel knob until the vertical bar labeled "1" is just barely visible against the black border. Vertical bar "0" must not be visible.

Maximum Intensity Adjustment

Photometer warm-up time: 30 minutes

This adjustment ensures that the light output at the 100% intensity level is equal to, or less than 150 Nits. The level is set using a photometer to measure the output light.

Caution If you operate the display at intensities higher than 150 Nits, you may reduce the life of the display.

5. Press the top softkey.
The analyzer display should have an all white screen.
6. Set the photometer probe to NORMAL. Press **POWER** on the photometer to switch it on and allow 30 minutes of warm-up time. Zero the photometer according to the manufacturer's instructions.
7. Center the photometer on the analyzer display as shown in Figure 3-3.

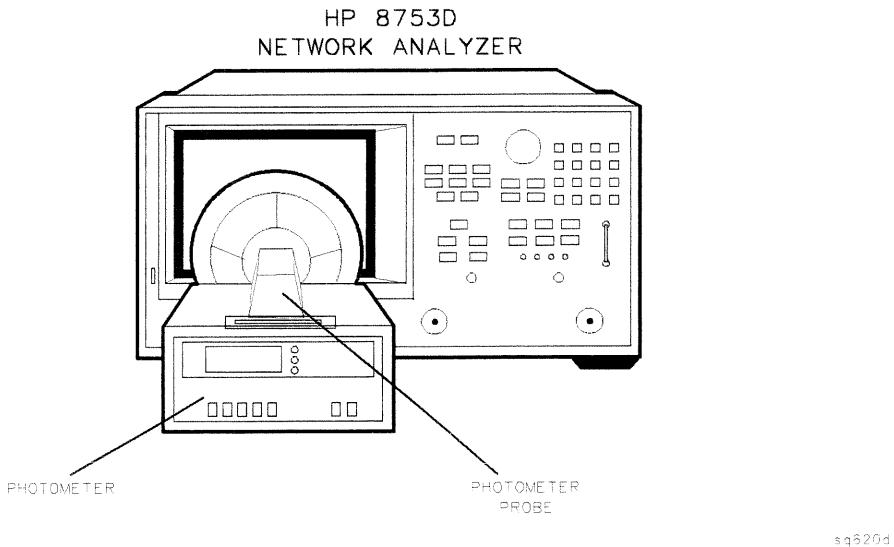


Figure 3-3. Maximum Intensity Adjustment Setup

Note

The intensity levels are read with a display bezel installed. The glass filter transmits 60% of the display light, therefore 90 Nits would be 150 Nits without the bezel installed.

8. Adjust the analyzer front panel knob to the maximum (clockwise) position.
 - If the photometer registers greater than 90 Nits (or 150 Nits without the bezel), turn the front panel knob until a reading of no more than 90 Nits, registers on the photometer.
 - If the photometer registers a reading of less than 90 Nits (or 150 Nits without the bezel), and greater than 60 Nits (or 100 without the bezel), proceed to "Operating Default Intensity Adjustment."
 - If the photometer registers a reading of less than 60 Nits (or 100 Nits without the bezel), the display is faulty.

Operating Default Intensity Adjustment

This adjustment sets the preset default level of the display intensity. If you switch the power off and on, the analyzer uses this default level to ensure that the display is visible and eliminates concern that the display may not be functioning.

9. Press the top softkey on the analyzer to bring up the next display adjustment mode.
10. Center the photometer on the analyzer display as shown in Figure 3-3.
11. Adjust the analyzer front panel knob until the photometer registers 60 Nits (or 100 Nits without bezel installed).
12. Press the top softkey on the analyzer and observe the display:
 - If **DONE** is displayed on the analyzer, the adjustment is done. This completes the series of three Display Intensity Adjustment Procedures.
 - If **FAIL** is displayed on the analyzer, repeat the three “Display Intensity Adjustment (Test 49).” If the analyzer still fails the adjustment routine, refer to the “Start Troubleshooting Here” chapter to isolate the problem.

IF Amplifier Correction Constants (Test 51)

Required Equipment and Tools

Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Additional Required Equipment for 50Ω Analyzers

RF Cable - (50Ω) 24-inch, APC-7	HP P/N 8120-4779
---------------------------------------	------------------

Additional Required Equipment for 75Ω Analyzers

RF Cable - (75Ω) 24-inch, Type-N	HP P/N 8120-2408
--	------------------

Analyzer warm-up Time: 30 minutes.

These correction constants compensate for possible discontinuities of signal greater than -30 dBm.

1. Connect the RF cable from Port 1 to Port 2 of the analyzer.
2. Press **PRESET** **SYSTEM** SERVICE MENU TESTS **51** **x1** EXECUTE TEST YES
CONTINUE .
3. Observe the analyzer for the results of the adjustment routine:
 - If DONE is displayed, you have completed this procedure.
 - If FAIL is displayed, check that the RF cable is connected from Port 1 to Port 2. Then repeat this adjustment routine.
 - If the analyzer continues to fail the adjustment routine, refer to the "Digital Control Troubleshooting" chapter.

ADC Offset Correction Constants (Test 52)

Analyzer warm-up time: 30 minutes.

These correction constants improve the dynamic accuracy by shifting small signals to the most linear part of the ADC quantizing curve.

1. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [52] [x1] EXECUTE TEST YES .

Note This routine takes about three minutes.

2. Observe the analyzer for the results of the adjustment routine:

- If the analyzer displays ADC Ofs Cor DONE, you have completed this procedure.
- If the analyzer displays ADC Ofs Cor FAIL, refer to the “Digital Control Troubleshooting” chapter.

Sampler Magnitude and Phase Correction Constants (Test 53)

Required Equipment and Tools

Power Meter	HP 437B or HP 438A
HP-IB Cable	HP 10833A
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Mat and Earth Ground Wire	HP P/N 9300-0797

Additional Required Equipment for 50Ω Analyzers

Power Sensor	HP 8482A
Power Sensor (for Option 006 analyzers)	HP 8481A
Cable, (50Ω) 24-inch, APC-7 (2)	HP P/N 8120-4779
Adapter APC-7 to Type-N(f)	HP 11524A

Additional Required Equipment for 75Ω Analyzers

Power Sensor	HP 8483A Option H03
Cable, (75Ω) 24-inch, Type-N (2)	HP 8120-2408

Analyzer warm-up time: 30 minutes.

This adjustment procedure corrects the overall flatness of the microwave components that make up the analyzer receiver and test separation sections. This is necessary for the HP 8753D to meet the published test port flatness.

1. If you just completed "Source Correction Constants (Test 47)," continue this procedure with step 8.
2. Press **[PRESET] [LOCAL] SYSTEM CONTROLLER**.
3. Press **[LOCAL] SET ADDRESSES ADDRESS: P MTR/HPIB**. The default power meter address is 13. Refer to the power meter manual as required to observe or change its HP-IB address.
4. Press **POWER MTR:438A/437** to toggle between the 438A/437 and 436A power meters. Choose the appropriate model number.

Note

If you are using the HP 438A power meter, connect the HP 8482A power sensor to channel A, and the HP 8481A power sensor to channel B.

Power Sensor Calibration Factor Entry

5. Press **SYSTEM SERVICE MENU TEST OPTIONS LOSS/SENSR LISTS**
CAL FACTOR SENSOR A to access the calibration factor menu for power sensor A (HP 8482A for 50Ω analyzers, or HP 8483A Option H03 for 75Ω analyzers).
6. Build a table of up to twelve points (twelve frequencies with their calibration factors). To enter each point, follow these steps:
 - a. Press **ADD FREQUENCY**.
 - b. Input a frequency value and then press the appropriate key (**G/n**, **M/μ**, or **k/m**).
 - c. Press **DONE** and enter the calibration factor percentage that corresponds to the frequency you entered.
The cal factor and frequency values are found on the back of the sensor. If you make a mistake, press **←** and re-enter the correct value.
 - d. Press **DONE** to complete the data entry for each point.

Note The following terms are part of the sensor calibration menu:

SEGMENT allows you to select a frequency point.

EDIT allows you to edit or change a previously entered value.

DELETE allows you to delete a point from the sensor cal factor table.

ADD allows you to add a point into the sensor cal factor table.

CLEAR LIST allows you to erase the entire sensor cal factor table.

DONE allows you to complete the points entry of the sensor cal factor table.

7. **For Option 006 Instruments Only:** Zero and calibrate the power meter and HP 8481A power sensor. Then press CAL FACTOR SENSOR B to create a power sensor calibration table for power sensor B (HP 8481A), using the softkeys mentioned above.

Determine the Insertion Loss of the Cable at 1 GHz

8. Press [PRESET] [MEAS] Trans : FWD S21(B/R) .
9. Press [CENTER] [1] [G/n] [x1] [SPAN] [50] [M/ μ] [x1].
10. Press [CAL] CAL KIT SELECT CAL KIT CAL KIT : 7mm RETURN RETURN CALIBRATE MENU RESPONSE .
11. Connect the 24 inch cable from Port 1 to Port 2, as shown in Figure 3-4.

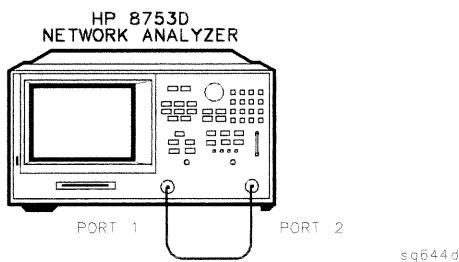


Figure 3-4. First Connections for Insertion Loss Measurement

12. Press THRU and when the analyzer is done measuring the thru.
13. Press [SAVE/RECALL] SAVE STATE to save the calibration that you just made.
14. Make the connections as shown in Figure 3-5.

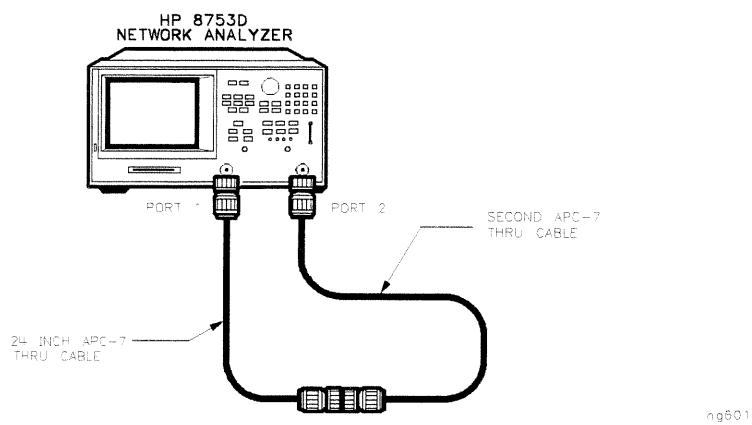


Figure 3-5. Second Connections for Insertion Loss Measurement

15. Press **SCALE REF** **SCALE/DIV** **[1]** **x1** **MARKER** **MARKER 1** **[1]** **G/n** **[x1]**. Record the insertion loss of the second thru cable as shown in the upper-right corner of the analyzer display.

3-24 Adjustments and Correction Constants

Sampler Correction Constants Routine

16. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [53] [x1] EXECUTE TEST and answer YES at the prompt.
17. When the analyzer displays CONNECT <3 GHz SENSOR A TO PORT 1, make the connections as shown in Figure 3-6.

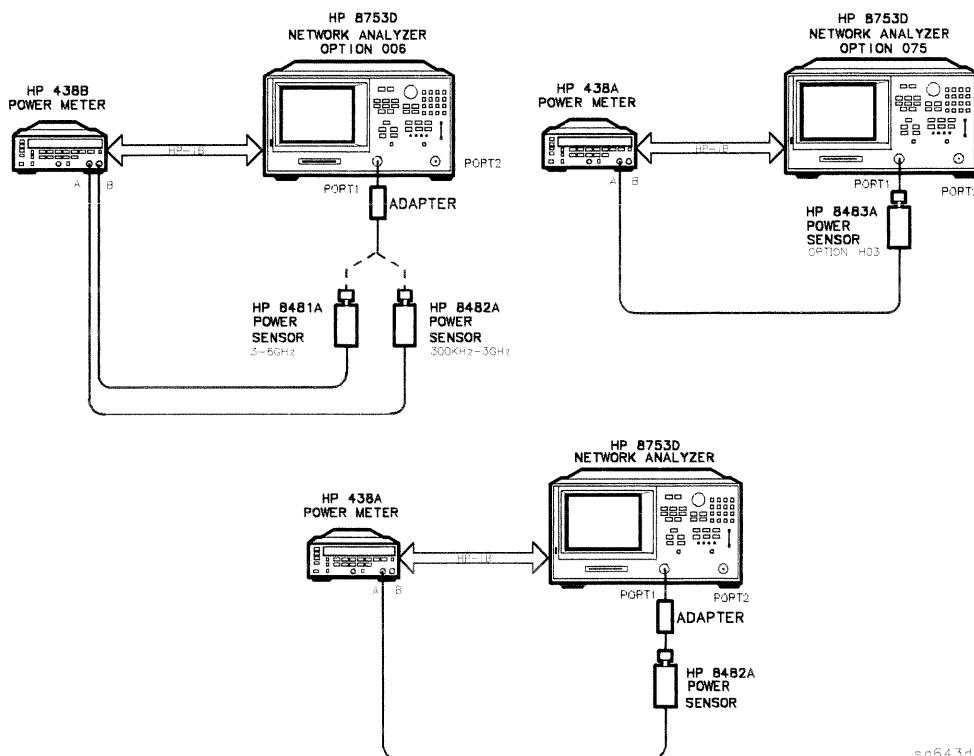


Figure 3-6. Connections for Sampler Correction Routine

18. Press **CONTINUE** to start the test. This part of the test will take about seven minutes.
- If the analyzer displays Sampler Cor - FAIL, check the following:
 - a. The HP-IB address of your power meter is set at 13. Then rerun this routine ("Sampler Correction Constants Routine").
 - b. The HP 8482A power sensor is connected to Port 1. Rerun this routine ("Sampler Correction Constants Routine").
19. **For Option 006 Instruments Only:** When the analyzer displays CONNECT 6 GHz SENSOR B TO PORT 1, make the connections as shown in Figure 3-7. Then press **CONTINUE**. This part of the test will take about 20 seconds.

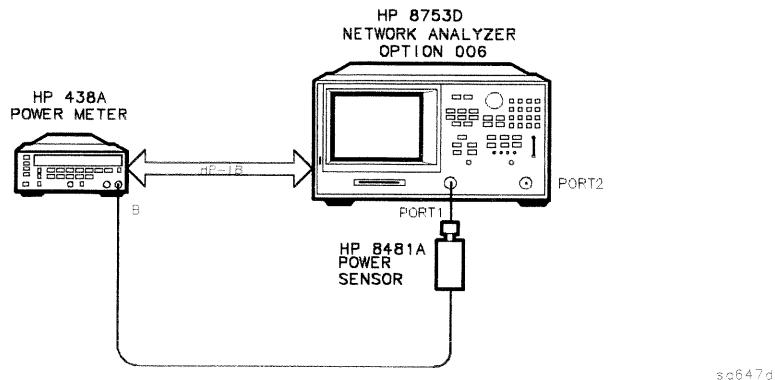


Figure 3-7. Connections for Sampler Correction at 6 GHz

20. When the analyzer displays CONNECT <3 GHz SENSOR A TO PORT 2, make the connections as shown in Figure 3-8.

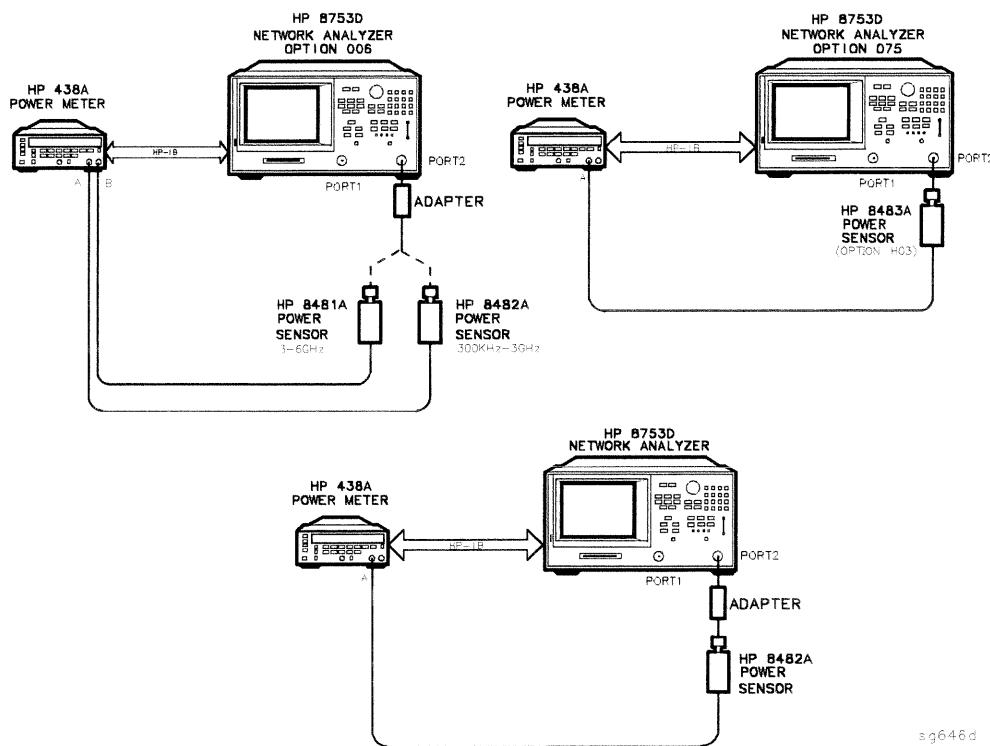


Figure 3-8. Connections for Sampler Correction at Port 2

21. Press **CONTINUE**. This part of the test will take about 10 minutes.
22. **For Option 006 Instruments Only:** When the analyzer displays **CONNECT 6 GHz SENSOR TO PORT 2**, make the connections as shown in Figure 3-9. Then press **CONTINUE**. This part of the test will take about 20 seconds.

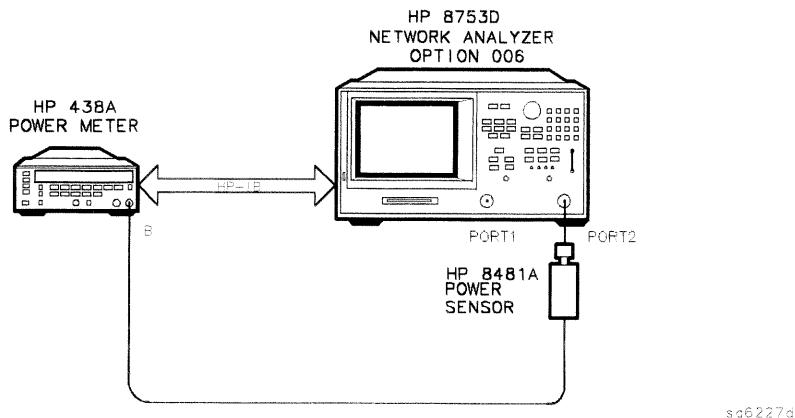


Figure 3-9. Connections for Sampler Correction at Port 2 for 6 GHz

23. When the analyzer displays CONNECT PORT 1 TO PORT 2, make the connections of the second thru cable (of which you have determined its insertion loss) as shown in Figure 3-10.

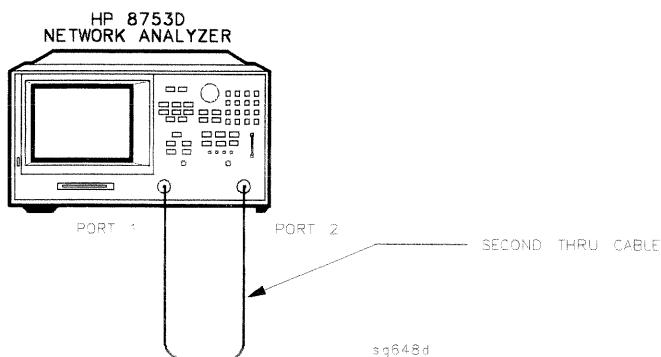


Figure 3-10. Connections for the Second Thru Cable

24. Press **CONTINUE**.
25. Enter the insertion loss of the thru cable (determined in step 14) and press **CONTINUE**. For example, if the insertion loss of the thru cable at 1 GHz is found to be 0.25 dB then press **[25] [x1]**.

3-28 Adjustments and Correction Constants

26. When the analyzer completes the test, observe the display for the results:
- If you see Sampler Cor - DONE, you have completed this procedure.
 - If you see Sampler Cor - FAIL, it is necessary to adjust the sampler gain offset values, which are stored in EEPROM.

A Channel Sampler

- a. Access the first address by pressing [SYSTEM] SERVICE MENU PEEK/POKE PEEK/POKE ADDRESS [5242936] [x1].
 - b. Enter the new value at the accessed address by pressing POKE [46] [x1].
 - c. Access the second address by pressing PEEK/POKE ADDRESS [5242938] [x1].
 - d. Enter the new value at the accessed address by pressing POKE [248] [x1].
 - e. Press [PRESET] for the analyzer to use the new values.
 - f. Repeat the "Sampler Correction Constants Routine."
- If the analyzer continues to fail this adjustment routine, refer to the "Source Troubleshooting" chapter.

B Channel Sampler

- a. Access the first address by pressing [SYSTEM] SERVICE MENU PEEK/POKE PEEK/POKE ADDRESS [5242940] [x1].
 - b. Enter the new value at the accessed address by pressing POKE [46] [x1].
 - c. Access the second address by pressing PEEK/POKE ADDRESS [5242942] [x1].
 - d. Enter the new value at the accessed address by pressing POKE [248] [x1].
 - e. Press [PRESET] for the analyzer to use the new values.
 - f. Repeat the "Sampler Correction Constants Routine."
- If the analyzer continues to fail this adjustment routine, refer to the "Source Troubleshooting" chapter.

R Channel Sampler

- a. Access the first address by pressing **SYSTEM** SERVICE MENU PEEK/POKE PEEK/POKE ADDRESS **5242944** **x1**.
 - b. Enter the new value at the accessed address by pressing **POKE** **62** **x1**.
 - c. Access the second address by pressing PEEK/POKE ADDRESS **5242946** **x1**.
 - d. Enter the new value at the accessed address by pressing **POKE** **128** **x1**.
 - e. Press **RESET** for the analyzer to use the new values.
 - f. Repeat the "Sampler Correction Constants Routine."
- If the analyzer continues to fail this adjustment routine, refer to the "Source Troubleshooting" chapter.

Cavity Oscillator Frequency Correction Constants (Test 54)

Required Equipment and Tools

Low-pass Filter	HP P/N 9135-0198
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Additional Required Equipment for 50Ω Analyzers

Adapter APC-7 to 3.5 mm (m)	HP P/N 1250-1746
Adapter APC-7 to 3.5 mm (f)	HP P/N 1250-1747
RF Cable Set APC-7.....	HP 11857D

Additional Required Equipment for 75Ω Analyzers

Adapter APC-3.5 (f) to Type-N (f)	HP P/N 1250-1745
Adapter APC-3.5 (m) to Type-N (f)	HP P/N 1250-1750
RF Cable Set 50Ω, Type-N	HP 11851B
Minimum Loss Pad 50Ω to 75Ω (2)	HP 11852B

Analyzer warm-up Time: 30 minutes.

The nominal frequency of the cavity oscillator is 2.982 GHz, but it varies with temperature. This procedure determines the precise frequency of the cavity oscillator at a particular temperature by identifying a known spur.

Note

You should perform this procedure with the recommended filter, or a filter with at least 50 dB of rejection at 2.9 GHz and a passband which includes 800 MHz. The filter makes spur identification substantially faster and more reliable.

With the filter, you need to distinguish between only two spurs, each of which should be 10 dB to 20 dB (3 to 4 divisions) above the trace noise.

Without the filter, you need to distinguish the target spur between four or five spurs, each of which may be 0.002 to 0.010 dB (invisible to 2 divisions) above or below the trace noise.

Perform the first five steps of the procedure at least once for familiarization before trying to select the target spur (especially if you are not using a filter).

1. Connect the equipment shown in Figure 3-11.

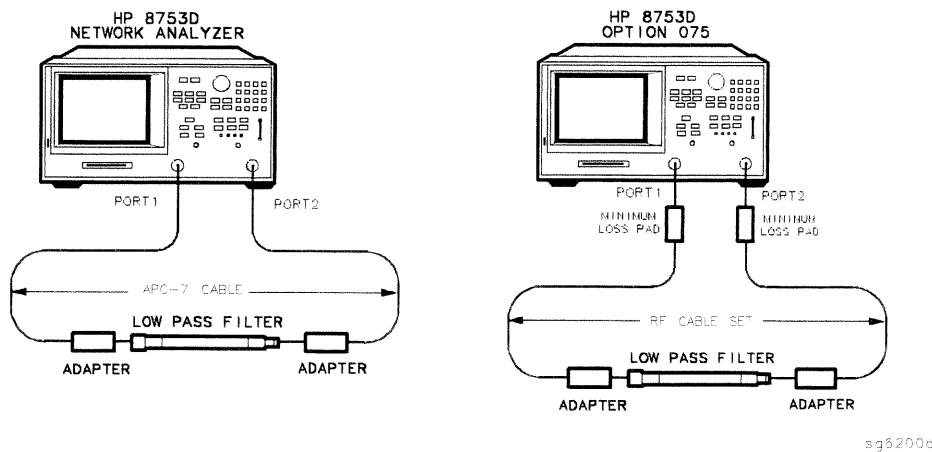


Figure 3-11.

Setup for Cavity Oscillator Frequency Correction Constant Routine

2. Press **PRESET** **SYSTEM** **SERVICE MENU TESTS** **[54]** **x1** **EXECUTE TEST YES**.

During this adjustment routine, you will see several softkeys:

CONTINUE

sweeps the current frequency span; you may press it repeatedly for additional sweeps of the current frequency span

NEXT

sweeps the next frequency span (2 MHz higher)

SELECT

enters the value of the marker (which you have placed on the spur) and exits the routine

ABORT

exits the routine

3. Press **CONTINUE** to sweep the first frequency span three times. Each new span overlaps the previous span by 3 MHz (the center frequency increases by 2 MHz; the span is 5 MHz). Therefore, anything visible on the right half of the screen of one set of sweeps will appear on the left half or center of the screen when you press **NEXT**.

3-32 Adjustments and Correction Constants

4. Press **NEXT** repeatedly. Watch the trace on each sweep and try to spot the target spur. With the filter, the target spur will be one of two obvious spurs (see Figure 3-12). Without the filter (not recommended), the target spur will be one of four or five less distinct spurs as shown in Figure 3-13 and Figure 3-14. When the center frequency increases to 2994.999 MHz, and you have not “selected” the target spur, **Cav Osc Cor FAIL** will appear on the display.

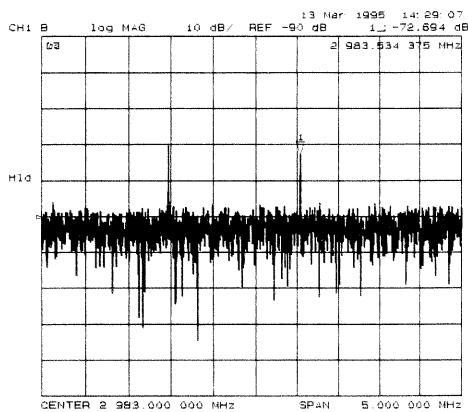


Figure 3-12. Typical Display of Spurs with a Filter

Spur Search Procedure with a Filter

5. Press **EXECUTE TEST YES CONTINUE** and the other softkeys as required to observe and mark the target spur. The target spur will appear to the right of a second spur, similar to Figure 3-12.
6. Rotate the front panel knob to position the marker on the spur and then press **SELECT**.
7. Observe the analyzer for the results of this adjustment routine:
 - If the analyzer displays **Cav Osc Cor DONE**, you have completed this procedure.
 - If the analyzer does not display **DONE**, repeat this procedure.
 - If the analyzer continues not to display **DONE**, refer to the “Source Troubleshooting” chapter.

Spurs Search Procedure without a Filter

8. Press EXECUTE TEST YES CONTINUE and the other softkeys as required to observe and mark the target spur.
9. The target spur will appear in many variations. Often it will be difficult to identify positively; occasionally it will be nearly impossible to identify. Do not hesitate to press CONTINUE as many times as necessary to thoroughly inspect the current span.

The target spur usually appears as one of a group of four evenly spaced spurs as in Figure 3-13. The target spur is on the right most spur (fourth from the left). On any particular sweep, one, any, or all of the spurs may be large, small, visible, above or below the reference line.

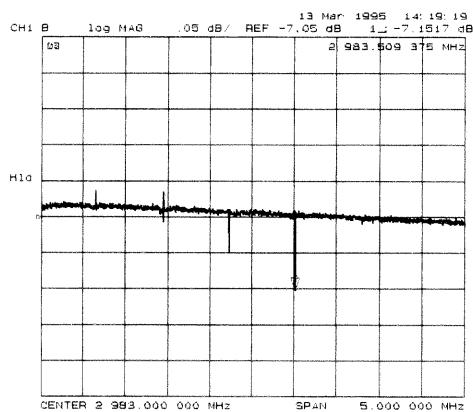


Figure 3-13. Typical Display of Four Spurs without a Filter

On occasion the largest spur appears as one of a group of five evenly spaced spurs as shown in Figure 3-14. The target spur is again the fourth from the left (not the fifth, right-most spur).

3-34 Adjustments and Correction Constants

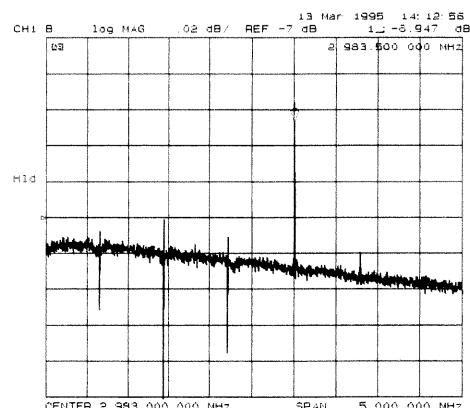


Figure 3-14. Target Spur Is Fourth in Display of Five Spurs

Figure 3-15 shows another variation of the basic four spur pattern: some up, some down, and the target spur itself almost indistinguishable.

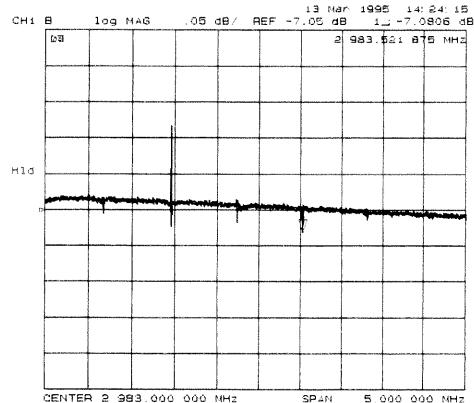


Figure 3-15. Target Spur Is Almost Invisible

10. Rotate the front panel knob to position the marker on the target spur. Then press **SELECT** and observe the analyzer for the results of the adjustment routine:
 - If the analyzer displays **Cav Osc Cor DONE**, you have completed this procedure.
 - If the analyzer displays **FAIL**, refer to “Source Troubleshooting.”

3-36 Adjustments and Correction Constants

Serial Number Correction Constants (Test 55)

Analyzer warm-up time: 5 minutes.

This procedure stores the analyzer serial number in the A9 CPU assembly EEPROMs.

Caution Perform this procedure *ONLY* if the A9 CPU assembly has been replaced.

1. Record the ten character serial number that is on the HP 8753D rear panel identification label.
2. Press **[PRESET] DISPLAY MORE TITLE ERASE TITLE** to erase the HP logo.
3. Enter the serial number by rotating the front panel knob to position the arrow below each character of the instrument serial number, and then pressing **SELECT LETTER** to enter each letter. Enter a total of ten characters: four digits, one letter, and five final digits.
Press **BACKSPACE** if you made a mistake.
4. Press **DONE** when you have finished entering the title.

Caution You *CANNOT* correct mistakes after you perform step 5, unless you contact the factory for a clear serial number keyword. Then you must perform the "Options Correction Constants" procedure and repeat this procedure.

5. Press **[SYSTEM] SERVICE MENU TESTS [55] [x1] EXECUTE TEST YES**.

6. Observe the analyzer for the results of the routine:

- If the analyzer displays the message **Serial Cor DONE**, you have completed this procedure.
- If the analyzer does not display **DONE**, then either the serial number that you entered in steps 3 and 4 did not match the required format or a serial number was already stored. Check the serial number recognized by the analyzer:
 - a. Press **[PRESET] [SYSTEM] SERVICE MENU FIRMWARE REVISION**.
 - b. Look for the serial number displayed on the analyzer screen.
 - c. Rerun this adjustment test.
- If the analyzer continues to fail this adjustment routine, contact your nearest HP Sales and Service Office. Refer to Chapter 15.

Option Numbers Correction Constants (Test 56)

This procedure stores instrument option(s) information in A9 CPU assembly EEPROMs. You can also use this procedure to remove a serial number, with the unique keyword, as referred to in "Serial Number Correction Constant."

1. Remove the instrument top cover and record the keyword label(s) that are on the display assembly. Note that each keyword is for EACH option installed in the instrument.
 - If the instrument does not have a label, then contact your nearest Hewlett-Packard Sales and Service Office. Refer to Chapter 15. Be sure to include the full serial number of the instrument.
2. Press **PRESET** **DISPLAY** MORE TITLE ERASE TITLE.
3. Enter the keyword by rotating the front panel knob to position the arrow below each character of the keyword, and then pressing **SELECT LETTER** to enter each letter.
Press **BACKSPACE** if you made a mistake.
4. Press **DONE** when you have finished entering the title.

Caution Do not confuse "I" with "1" or "O" with "0" (zero).

5. Press **SYSTEM** SERVICE MENU TESTS **56** **(x1)** EXECUTE TEST YES.
6. Observe the analyzer for the results of the adjustment routine:
 - If the analyzer displays Option Cor DONE, you have completed this procedure.
 - If the analyzer has more than one option, repeat steps 2 through 5 to install the remaining options.
 - If the analyzer displays Option Cor FAIL, check the keyword used in step 3 and make sure it is correct. Pay special attention to the letters "I" or "0", the numbers "1" or "0" (zero). Repeat this entire adjustment test.
 - If the analyzer continues to fail the adjustment routine, contact your nearest HP Sales and Service Office. Refer to Chapter 15.

Calibration Kit Default Correction Constants (Test 57)

This internal adjustment test writes default calibration kit definitions (device model coefficients) into EEPROM's.

1. Press **[PRESET]** **[SYSTEM]** SERVICE MENU TESTS **[57]** **[x1]** EXECUTE TEST YES.
2. Observe the analyzer for the results of the adjustment routine:
 - If the analyzer displays Cal Kit Def DONE, press **[PRESET]**, and you have completed this procedure.
 - If the analyzer does not display DONE, contact your nearest HP Sales and Service Office.

Initialize EEPROMs (Test 58)

This service internal test performs the following functions:

- *destroys* all correction constants and all un-protected options
- initializes certain EEPROM address locations to zeroes
- replaces the display intensity correction constants with default values.

Note This routine *WILL NOT* alter the serial number or Options 002, 006 and 010 correction constants.

1. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [58] [x1] EXECUTE TEST YES .
2. Restore the analyzer options in the EEPROMs:
 - If you have the correction constants backed up on a disk, perform these steps:
 - a. Place the disk in the analyzer disk drive and press [SAVE/RECALL] SELECT DISK INTERNAL DISK .
 - b. Use the front panel knob to highlight the filename that represents your serial number.
 - c. Press RETURN RECALL STATE [PRESET].
 - If you don't have the correction constants backed up on a disk, run all the internal service routines in the following order:
 - Display Intensity (Test 49)
 - Source Default Correction Constants (Test 44)
 - Source Pretune Correction Constants (Test 45)
 - Analog Bus Correction Constants (Test 46)
 - Source Pretune Correction Constants (Test 48)
 - Calibration Kit Default Correction Constants (Test 57)
 - ADC Offset Correction Constants (Test 52)
 - RF Output Power Correction Constants (Test 47)
 - Sampler Magnitude and Phase Correction Constants (Test 53)
 - IF Amplifier Correction Constants (Test 51)
 - Cavity Oscillator Frequency Correction Constants (Test 54)

EEPROM Backup Disk Procedure

Required Equipment and Tools

3.5-inch Floppy Disk	HP 92192A (box of 10)
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

The correction constants, that are unique to your instrument, are stored in EEPROM on the A9 controller assembly. By creating an EEPROM backup disk, you will have a copy of all the correction constant data should you need to replace or repair the A9 assembly.

1. Insert a 3.5-inch disk into the analyzer disk drive.
2. If the disk is not formatted, follow these steps:
 - a. Press **[SAVE/RECALL] FILE UTILITIES FORMAT DISK**.
 - b. Select the format type:
 - To format a LIF disk, select **FORMAT:LIF**.
 - To format a DOS disk, select **FORMAT:DOS**.
 - c. Press **FORMAT INT DISK** and answer **YES** at the query.
3. Press **[SYSTEM] SERVICE MENU SERVICE MODES MORE STORE EEPR ON [SAVE/RECALL] SELECT DISK INTERNAL DISK RETURN SAVE STATE**.

Note The analyzer creates a default file "FILE0". The filename appears in the upper-left corner of the display. The file type "ISTATE(E)" indicates that the file is an instrument-state with EEPROM backup.

4. Press **FILE UTILITIES RENAME FILE ERASE TITLE**. Use the front panel knob and the **SELECT LETTER** softkey (or an external keyboard) to rename the file "FILE0" TO "N12345" where 12345 represents the last 5 digits of the instrument's serial number. (The first character in the filename must be a letter.) When you are finished renaming the file, press **DONE**.

5. Write the following information on the disk label:
 - analyzer serial number
 - today's date
 - "EEPROM Backup Disk"

How to Retrieve Correction Constant Data from the EEPROM Backup Disk

1. Insert the "EEPROM Backup Disk" into the HP 8753D disk drive.
2. Make sure the A9 CC jumper is in the ALTER position.
3. Press **[SAVE/RECALL] SELECT DISK INTERNAL DISK**. Use the front panel knob to highlight the file "N12345" where N12345 represents the file name of the EEPROM data for the analyzer. On the factory shipped EEPROM backup disk, the filename is FILE1.
4. Press **RETURN RECALL STATE** to down load the correction constants data into the instrument EEPROM's.
5. Perform "Serial Number Correction Constants (Test 55)," and, if applicable, "Option Numbers Correction Constant (Test 56)."
6. Press **[PRESET]** and verify that good data was transferred to EEPROM by performing a simple measurement.
7. Move the A9 CC jumper back to its NORMAL position when you are done working with the instrument.

Vertical Position and Focus Adjustments

Required Equipment and Tools

Non-Conductive Flat Head Screwdriver, 2-inches	HP P/N 8830-0024
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Analyzer warm-up time: 30 minutes.

Use this procedure to adjust the vertical position and focus of the analyzer color display.

Caution These are the only display adjustments. Any other adjustments to the color display will *VOID* the warranty.

Vertical Adjustment Procedure

1. Remove the left-rear bumpers and left side panel.

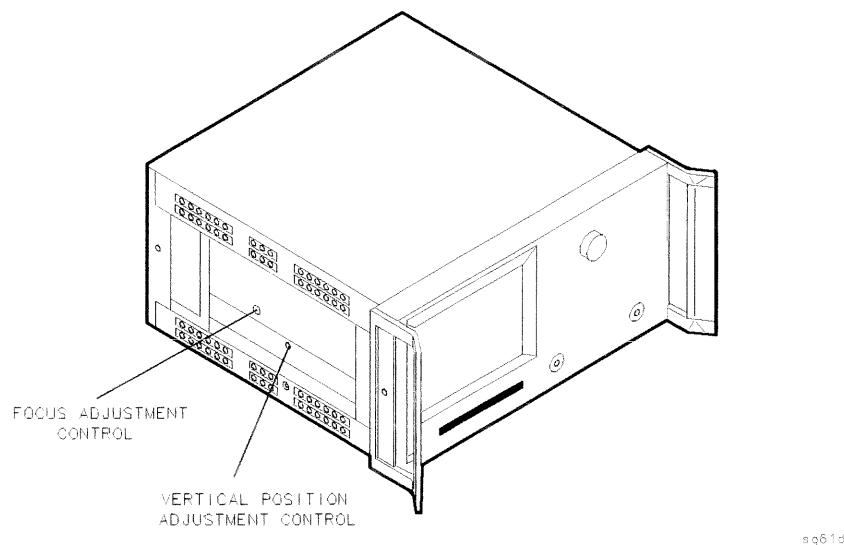


Figure 3-16. Vertical Position and Focus Adjustment Locations

2. Insert the flat head screw driver into the vertical position hole.
3. Adjust the control until the softkey labels are aligned with the softkeys.

Focus Adjustment Procedure

4. Use the screw driver in step 3 to adjust the focus until the display has the most readability.

Display Degaussing (Demagnetizing)

Required Equipment and Tools

Any CRT Demagnetizer or Bulk Tape Eraser

Antistatic Wrist Strap HP P/N 9300-1367

Antistatic Wrist Strap Cord HP P/N 9300-0980

Static-control Table Mat and Earth Ground Wire HP P/N 9300-0797

As with all color monitors, the display is very susceptible to external magnetic fields. These fields can originate from many sources, including unshielded motors, metal frame tables, and from the earth itself. The usual symptom is a discoloration or slight dimming of the display usually near the top left corner of the display. If this problem is observed, remove the device causing the magnetic field.

In extreme cases, a total color shift may be observed; for example, a trace that was red may shift to green. This does not indicate a problem with the display; it is characteristic of all color displays.

In countries that use a 50 Hz, some 10 Hz jitters may be noticed.

1. If the display becomes magnetized, or if color purity is a problem, cycle the analyzer power several times. Leave the instrument off for at least 15 seconds before turning it on. This will activate the automatic degaussing circuitry in the display.
2. If the display color purity is still a problem, you must use a commercially available demagnetizer (either a CRT demagnetizer or a bulk tape eraser). Follow the manufacturer's instructions keeping in mind of the following:
 - At the first pass, do *NOT* place the demagnetizer closer than 4 inches (10 cm) from the face of the display while demagnetizing the display.
 - At the second pass, (if you did not completely demagnetize the display), move the demagnetizer to a slightly closer distance until the display is demagnetized.

Caution If you apply an excessively strong magnetic field to the display face, you can permanently destroy the display.

Fractional-N Frequency Range Adjustment

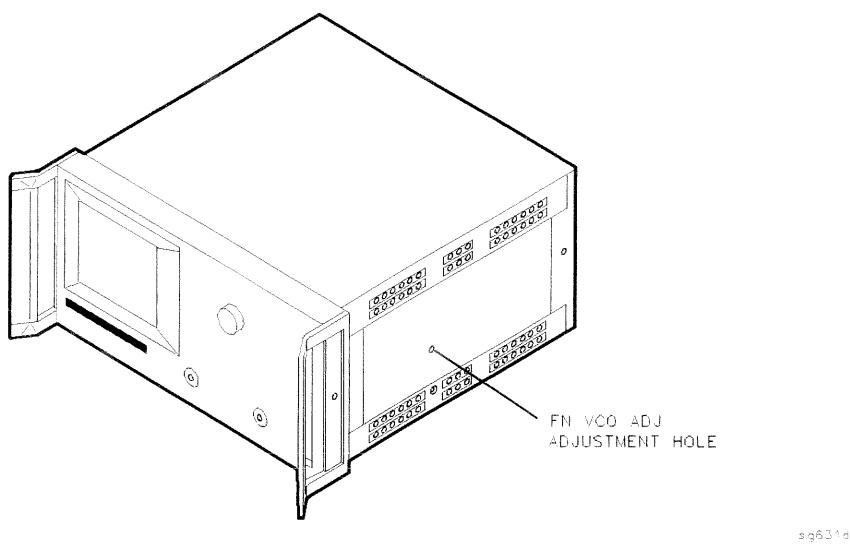
Required Equipment and Tools

Non-metallic Adjustment Tool	HP P/N 8830-0024
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Analyzer warm-up time: 30 minutes.

This procedure centers the fractional-N VCO (voltage controlled oscillator) in its tuning range to insure reliable operation of the instrument.

1. Remove the right-rear bumper and right side cover.
2. Press [PRESET] [DISPLAY] DUAL CHAN ON [SYSTEM] SERVICE MENU
ANALOG BUS ON [MENU] NUMBER of POINTS [11] [x1] COUPLED CH OFF.
3. Press [START] [36] [M/ μ] STOP [60.75] [M/ μ] [MENU] SWEEP TIME [12.5] [k/m]
[MEAS] ANALOG IN Aux Input [29] [x1] to observe the "FN VCO Tun" voltage.
4. Press [FORMAT] MORE REAL [SCALE REF] [6] [x1] REFERENCE VALUE [-7] [x1] to set and scale channel 1. Press [MARKER] to set the marker to the far right of the graticule.
5. Press [CHAN 2] [MENU] CW FREQ [31.0001] [M/ μ] SWEEP TIME [12.375] [k/m]
[MEAS] ANALOG IN Aux Input [29] [x1] to observe the "FN VCO Tun" voltage.
6. Press [FORMAT] MORE REAL [SCALE REF] [2] [x1] REFERENCE VALUE [6.77] [x1]
[MARKER] [6] [k/m] to set channel 2 and its marker.
7. Adjust the "FN VCO TUNE" (see Figure 3-17) with a non-metallic tool so that the channel 1 marker is as many divisions above the reference line as the channel 2 marker is below it. (See Figure 3-18.)



s3631d

Figure 3-17. Location of the FN VCO TUNE Adjustment

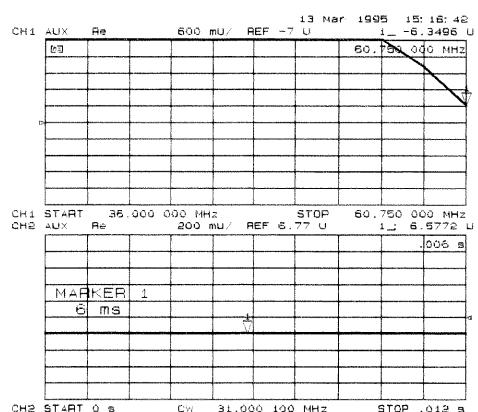


Figure 3-18. Fractional-N Frequency Range Adjustment Display

3-48 Adjustments and Correction Constants

8. To fine-tune this adjustment, press [PRESET] [MENU] CW FREQ [SYSTEM] SERVICE MENU ANALOG BUS ON SERVICE MODES FRACN TUNE ON to set "FRAC N TUNE" to 29.2 MHz.
9. Press [MEAS] ANALOG IN Aux Input [29] [x1] [MARKER] [FORMAT] MORE REAL [SCALE REF] REFERENCE VALUE [7] [x1].
10. Observe the analyzer for the results of this adjustment:
 - If the marker value is less than 7, you have completed this procedure.
 - If the marker value is greater than 7, readjust "FN VCO ADJ" to 7. Then perform steps 2 to 10 to confirm that the channel 1 and channel 2 markers are still above and below the reference line respectively.
 - If you cannot adjust the analyzer correctly, replace the A14 board assembly.

Frequency Accuracy Adjustment

Required Equipment and Tools

Spectrum Analyzer	HP 8563E
RF Cable, 50Ω Type-N, 24-inch	HP P/N 8120-4781
Non-metallic Adjustment Tool	HP P/N 8830-0024
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Additional Required Equipment for 50Ω Analyzers

Adapter APC-7 to Type-N (f)	HP 11525A
-----------------------------------	-----------

Additional Required Equipment for 75Ω Analyzers

Minimum Loss Pad	HP 11852B
------------------------	-----------

Analyzer warm-up time: 30 minutes.

This adjustment sets the VCXO (voltage controlled crystal oscillator) frequency to maintain the instrument's frequency accuracy.

1. Remove the upper-rear bumpers and analyzer top cover.
2. Connect the equipment as shown in Figure 3-19.

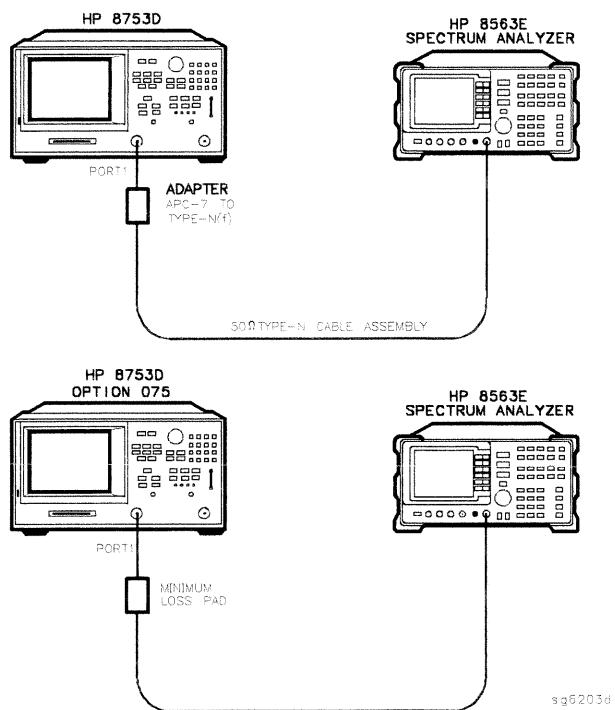


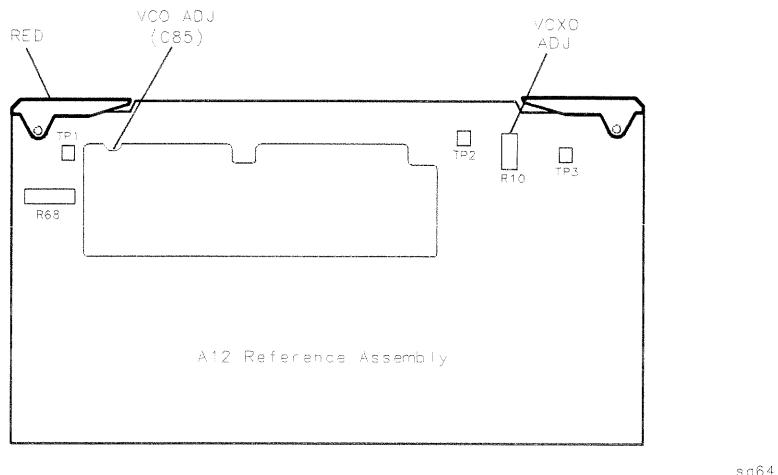
Figure 3-19. Frequency Accuracy Adjustment Setup

Note	Make sure that the spectrum analyzer and network analyzer references are <i>NOT</i> connected.
-------------	--

3. **For Option 1D5 Instruments Only:** Remove the BNC to BNC jumper that is connected between the "EXT REF" and the "10 MHz Precision Reference," as shown in Figure 3-21.
4. Set the spectrum analyzer measurement parameters as follows:

FREQUENCY	[2.9 G/n]	(or [5.9 G/n] for Option 006)
SPAN	[50 kHz]	
AMPLITUDE	REF LVL	[10 +dBm]
5. On the HP 8753D, press [PRESET] [MENU] CW FREQ [2.9 G/n] (or [5.9 G/n] for Option 006).

6. No adjustment is required when the spectrum analyzer measures 2.9 GHz \pm 50 kHz or 5.9 GHz \pm 50 kHz for Option 006. Otherwise, locate the A12 assembly (red extractors) and adjust the VCXO ADJ (see Figure 3-20) for a spectrum analyzer center frequency measurement of \pm 50 Hz.
7. Replace the A12 assembly if you are unable to adjust the frequency as specified. Repeat this adjustment test.



sg64d

Figure 3-20. Location of the VCXO ADJ Adjustment

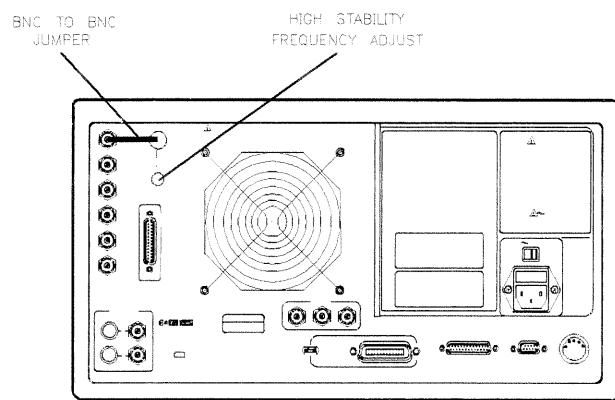
HP 8753D with Option 1D5 Only

8. Connect the BNC to BNC jumper between the "EXT REF" and the "10 MHz Precision Reference" as shown in Figure 3-21.
9. Use a flat-head screwdriver to remove the screw that covers the precision frequency adjustment as shown in Figure 3-21. Insert a narrow screwdriver and adjust the precision frequency reference potentiometer for a spectrum analyzer center frequency measurement of \pm 5 Hz.

Note

You may have to adjust the frequency 100 Hz to 250 Hz from the intended frequency (either higher or lower). Then replace the analyzer covers and wait 10 to 15 minutes before you check the center frequency.

3-52 Adjustments and Correction Constants



sg630d

Figure 3-21. High Stability Frequency Adjustment Location

10. Replace the A26 board assembly if you cannot adjust for a center frequency measurement of ± 50 Hz.

High/Low Band Transition Adjustment

Required Equipment and Tools

Non-metallic Adjustment Tool HP P/N 8830-0024

Analyzer warm-up time: 30 minutes.

This adjustment centers the VCO (voltage controlled oscillator) of the A12 reference assembly for high and low band operations.

1. Press [PRESET] [SYSTEM] SERVICE MENU ANALOG BUS ON [START] [11] [M/ μ] [STOP] [21] [M/ μ] to observe part of both the low and high bands on the analog bus.
2. Press [MEAS] ANALOG IN Aux Input [22] [x1] [FORMAT] MORE REAL [DISPLAY] DATA—MEM DATA-MEMORY to subtract the ground voltage from the next measurement.
3. Press [MEAS] ANALOG IN Aux Input [23] [x1] [MARKER] [11] [M/ μ].
4. Press [SCALE REF] [1] [x1] and observe the VCO tuning trace:
 - If the left half of trace = 0 ± 1000 mV and right half of trace = 100 to 200 mV higher (one to two divisions, see Figure 3-22): no adjustment is necessary.
 - If the adjustment is necessary, follow these steps:
 - a. Adjust the VCO tune (see Figure 3-23) to position the left half of the trace to 0 ± 125 mV. This is a very sensitive adjustment where the trace could easily go off of the screen.
 - b. Adjust the HBLB (see Figure 3-23) to position the right half of the trace 125 to 175 mV (about 1 to 1.5 divisions) higher than the left half.
 - Refer to “Source Troubleshooting” if you cannot perform the adjustment.

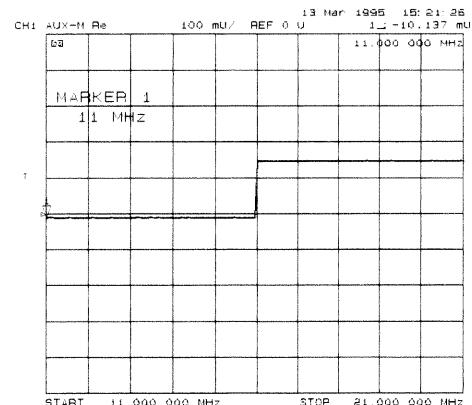


Figure 3-22. High/Low Band Transition Adjustment Trace

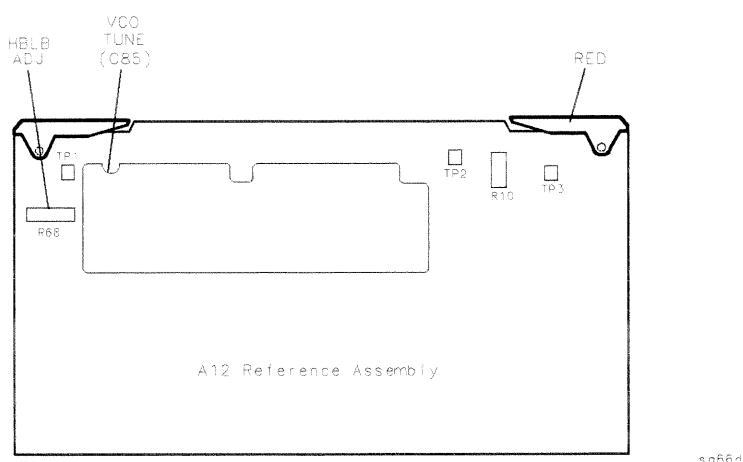


Figure 3-23. High/Low Band Adjustment Locations

Fractional-N Spur Avoidance and FM Sideband Adjustment

Required Equipment and Tools

Spectrum Analyzer	HP 8563E
HP-IB Cable	HP 10833A/B/C/D
RF Cable 50Ω, Type-N, 24-inch	HP P/N 8120-4781
Cable, 50Ω Coax, BNC (m) to BNC (m)	HP 10503A
Non-metallic Adjustment Tool	HP P/N 8830-0024
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Additional Required Equipment for 50Ω Analyzers

Adapter APC-7 to Type-N (f)	HP 11525A
-----------------------------------	-----------

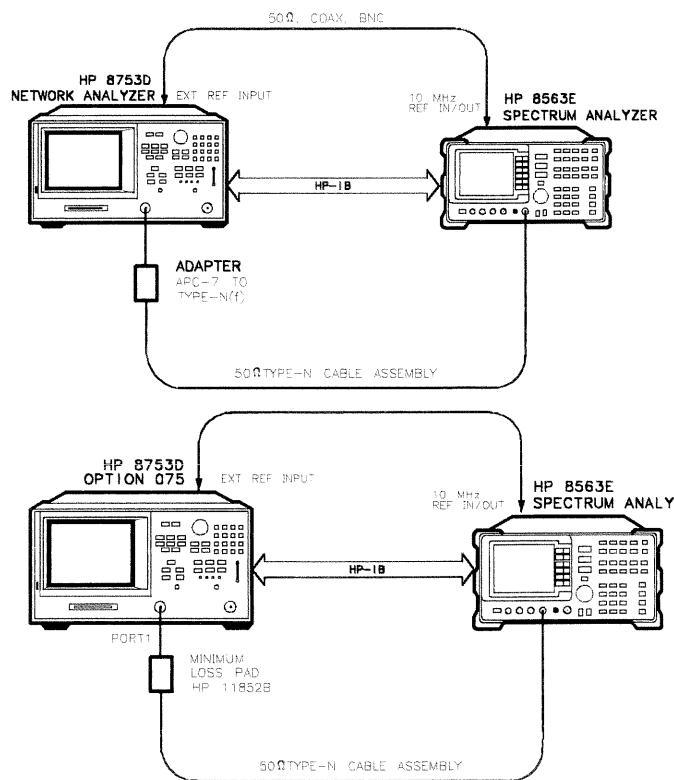
Additional Required Equipment for 75Ω Analyzers

Minimum Loss Pad	HP 11852B
------------------------	-----------

Analyzer warm-up time: 30 minutes.

This adjustment minimizes the spurs caused by the API (analog phase interpolator, on the fractional-N assembly) circuits. It also improves the sideband characteristics.

1. Connect the equipment as shown in Figure 3-24.
2. Make sure the instruments are set to their default HP-IB addresses:
HP 8753D = 16, Spectrum Analyzer = 18.



sg6202d

Figure 3-24.
Fractional N Spur Avoidance and FM Sideband Adjustment Setup

3. Set the spectrum analyzer measurement parameters as follows:

Reference Level	0 dBm
Resolution Bandwidth	100 Hz
Center Frequency	676.145105 MHz
Span	2.5 kHz

4. On the HP 8753D, press [PRESET] [MENU] CW FREQ [676.045105] [M/ μ].
5. Adjust the 100 kHz (R77) for a null (minimum amplitude) on the spectrum analyzer. The minimum signal may, or may not, drop down into the noise floor.

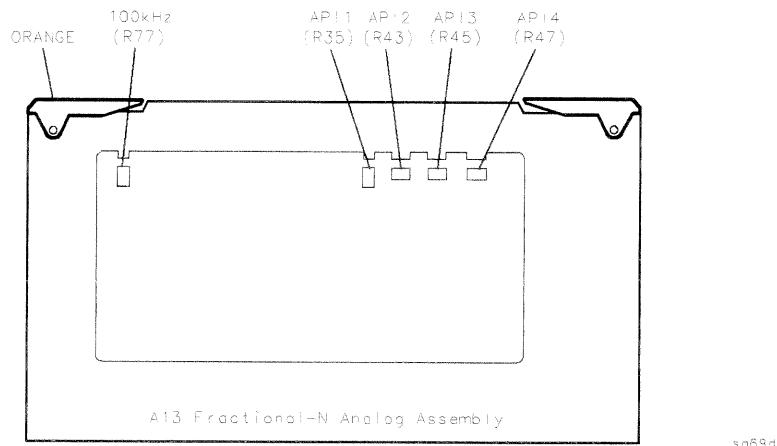


Figure 3-25. Location of API and 100 kHz Adjustments

6. On the spectrum analyzer, set the center frequency for 676.051105 MHz.
7. On the HP 8753D, press [MENU] CW FREQ [676.048105] [M/ μ].
8. Adjust the API1 (R35) for a null (minimum amplitude) on the spectrum analyzer.
9. On the spectrum analyzer, set the center frequency for 676.007515 MHz.
10. On the HP 8753D, press [MENU] CW FREQ [676.004515] [M/ μ].
11. Adjust the API2 (R43) for a null (minimum amplitude) on the spectrum analyzer.
12. On the spectrum analyzer, set the center frequency for 676.003450 MHz.
13. On the HP 8753D, press [MENU] CW FREQ [676.00045] [M/ μ].
14. Adjust the API3 (R45) for a null (minimum amplitude) on the spectrum analyzer.

3-58 Adjustments and Correction Constants

15. On the spectrum analyzer, set the center frequency for 676.003045 MHz.
16. On the HP 8753D, press **[MENU] CW FREQ [676.000045] [M/ μ]**.
17. Adjust the API4 (R47) for a null (minimum amplitude) on the spectrum analyzer.

In Case of Difficulty

18. If this adjustment can not be performed satisfactorily, repeat the entire procedure. Or else replace the A13 board assembly.

Source Spur Avoidance Tracking Adjustment

Required Equipment and Tools

BNC Alligator Clip Adapter	HP P/N 8120-1292
BNC to BNC Cable	HP P/N 8120-1840
Antistatic Wrist Strap	HP P/N 9300-1367
Antistatic Wrist Strap Cord	HP P/N 9300-0980
Static-control Table Mat and Earth Ground Wire	HP P/N 9300-0797

Analyzer warm-up time: 30 minutes.

This adjustment optimizes tracking between the YO (YIG oscillator) and the cavity oscillator when they are frequency offset to avoid spurs. Optimizing YO-cavity oscillator tracking reduces potential phase-locked loop problems.

1. Mate the adapter to the BNC cable and connect the BNC connector end to AUX INPUT on the HP 8753D rear panel. Connect the BNC center conductor alligator-clip to A11 TP10 (labeled ϕ ERR); the shield clip to A11 TP1 (GND) as shown in Figure 3-26.

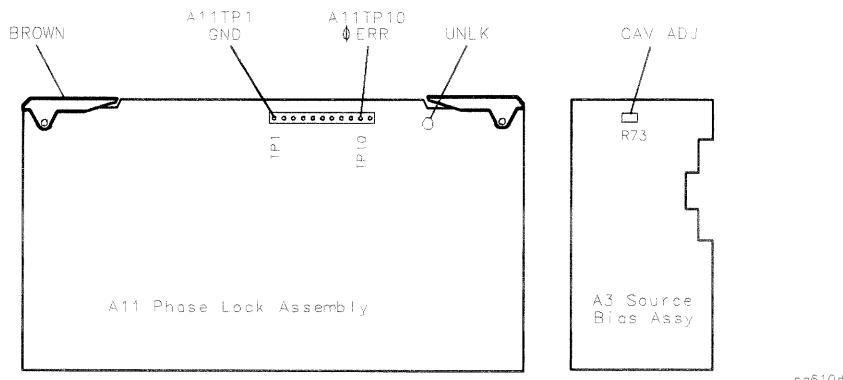


Figure 3-26. Location of A11 Test Points and A3 CAV ADJ Adjustments

2. Press [PRESET] [CENTER] 400 [M/ μ] [SPAN] 50 [M/ μ].
3. Press [SYSTEM] SERVICE MENU ANALOG BUS ON [MEAS]
ANALOG IN Aux Input [11] [x1].
4. Press [FORMAT] MORE REAL [SCALE REF] 10 [k/m] MARKER→REFERENCE.
5. Observe the phase locked loop error voltage:
 - If "Spikes" are not visible on the analyzer display (see Figure 3-27): no adjustment is necessary.
 - If "Spikes" are excessive (see Figure 3-27): adjust the CAV ADJ potentiometer (see Figure 3-26) on the A3 source bias assembly to eliminate the spikes.
 - If the "Spikes" persist, refer to the "Source Troubleshooting" chapter.

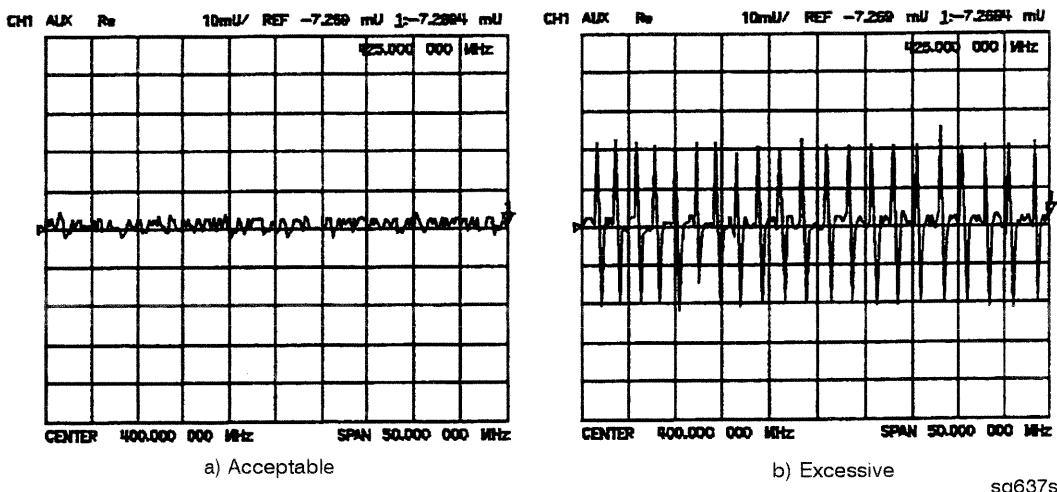


Figure 3-27. Display of Acceptable versus Excessive Spikes

Unprotected Hardware Option Numbers Correction Constants

Analyzer warm-up Time: None.

This procedure stores the instrument's unprotected option(s) information in A9 CPU assembly EEPROMs.

1. Make sure the A9 CC jumper is in the ALT (ALTER) position.
2. Record the installed options that are printed on the rear panel of the analyzer.
3. Press **SYSTEM SERVICE MENU PEEK/POKE PEEK/POKE ADDRESS**.
4. Refer to the table below for the address of each unprotected hardware option. Enter the address for the specific installed hardware option that needs to be enabled or disabled. Follow the address entry by **POKE [−1] [x1]**.
 - Pressing **POKE [−1] [x1]** after an entry enables the option.
 - Pressing **POKE [0] [x1]** after an entry disables the option.

Hardware Options	PEEK/POKE Address
1D5	5243250
011	5243256

5. Repeat steps 3 and 4 for all of the unprotected options that you want to enable.

6. After you have entered all of the instrument's hardware options, press the following keys:

SYSTEM SERVICE MENU FIRMWARE REVISION

7. View the analyzer display for the listed options.
8. When you have entered all of the hardware options, return the A9 CC jumper to the NRM (NORMAL) position.
9. Perform the "EEPROM Backup Disk Procedure" located on page 3-42.

In Case of Difficulty

If any of the installed options are missing from the list, return to step 2 and reenter the missing option(s).

Sequences for Mechanical Adjustments

The network analyzer has the capability of automating tasks through a sequencing function. The following adjustment sequences are available through InterNet.

- Fractional-N Frequency Range Adjustment
- High/Low Band Transition Adjustment
- Fractional-N Spur Avoidance and FM Sideband Adjustment

How to Load Sequences from Disk

1. Place the sequence disk in the analyzer disk drive.
2. Press **LOCAL SYSTEM CONTROLLER** **SEQUENCE** MORE
LOAD SEQUENCE FROM DISK READ SEQUENCE FILE TITLES .
3. Select any or all of the following sequence files by pressing:
 - Select **LOAD SEQ APIADJ** if you want to load the file for the “Fractional-N Spur Avoidance and FM Sideband Adjustment.”
 - Select **LOAD SEQ HBLBADJ** if you want to load the file for the “High/Low Band Transition Adjustment.”
 - Select **LOAD SEQ FNADJ** and **LOAD SEQ FNCHK** if you want to load the files for the “Fractional-N Frequency Range Adjustment.”

How to Set Up the Fractional-N Frequency Range Adjustment

1. Remove the right-rear bumpers and right side cover. This exposes the adjustment location in the sheet metal.
2. Press [PRESET] SEQUENCE X FNADJ (where X is the sequence number).
3. Adjust the “FN VCO TUNE” with a non-metallic tool so that the channel 1 marker is as many divisions above the reference line as the channel 2 marker is below it.
4. Press [PRESET] SEQUENCE X FNCHK (where X is the sequence number).
 - If the marker value is <7, you have completed this procedure.
 - If the marker value is >7, readjust “FN VCO TUNE” to 7. Then repeat steps 2,3, and 4 to confirm that the channel 1 and channel 2 markers are still above and below the reference line respectively.

How to Set Up the High/Low Band Transition Adjustments

1. Press [PRESET] SEQ X HBLBADJ (where X is the sequence number).
2. Observe the VCO tuning trace:
 - If the left half of trace = 0 ± 1000 mV and right half of trace = 100 to 200 mV higher (one to two divisions): no adjustment is necessary.
 - If the adjustment is necessary, follow these steps:
 - a. Remove the upper-rear bumpers and top cover, using a TORX screwdriver.
 - b. Adjust the VCO tune (A12 C85) to position the left half of the trace to 0 ± 125 mV. This is a very sensitive adjustment where the trace could easily go off of the screen.
 - c. Adjust the HBLB (A12 R68) to position the right half of the trace 125 to 175 mV (about 1 to 1.5 divisions) higher than the left half.

- Refer to "Source Troubleshooting" if you cannot perform the adjustment.

How to Set Up the Fractional-N Spur Avoidance and FM Sideband Adjustment

1. Press [PRESET] SEQUENCE X APIADJ (where X is the sequence number).
2. Remove the upper-rear corner bumpers and the top cover, using a TORX screwdriver.
3. Follow the directions on the analyzer display and make all of the API adjustments.

Sequence Contents

Sequence for the High/Low Band Transition Adjustment

—Sequence HBLBADJ sets the hi-band to low-band switch point.—

PRESET

SYSTEM

SERVICE MENU

ANALOG BUS ON

START 11 M/u

STOP 21 M/u

MEAS

ANALOG IN 22 x1 (A12 GND)

REAL

DISPLAY

DATA > MEM

DATA - MEM

MEAS

ANALOG IN 23 x1 (VCO TUNE)

MKR 11 M/u

SCALE/REF .1 x1

Sequences for the Fractional-N Frequency Range Adjustment

—Sequence FNADJ sets up A14 (FRAC N Digital) VCO.—

DISPLAY
DUAL CHAN ON
SYSTEM
SERVICE MENU
ANALOG BUS ON
MENU

NUMBER OF POINTS 11 x1
COUPLED CHAN OFF
START 36 M/u
STOP 60.75 M/u
MENU

SWEEP TIME 12.5 k/m
MEAS

ANALOG IN 29 x1 (FN VCO TUN)
SCALE/REF 0.6 x1

REAL REF VALUE -7 x1

MKR
CH 2
MENU
CW FREQ 31.0001 M/u
SWEEP TIME 12.375 k/m

MEAS
ANALOG IN 29 x1 (FN VCO TUN)
SCALE/REF .2 x1

REAL REF VALUE 6.77 x1

MKR 6 k/m

—Sequence FNCHK checks the VCO adjustment.—

MENU
CW FREQ 1 G/n
SYSTEM
SERVICE MENU
ANALOG BUS ON
SERVICE MODES
FRAC N TUNE ON

MEAS
ANALOG IN 29 x1
MKR

SCALE/REF
REF VALUE 7 x1

Sequences for the Fractional-N Avoidance and FM Sideband Adjustment

—Sequence APIADJ sets up the fractional-N API spur adjustments.—

```
TITLE
    SP 2.5KZ
PERIPHERAL HPIB ADDR
    18 x1
TITLE TO PERIPHERAL
WAIT x
    0 x1
TITLE
    AT 0DB
TITLE TO PERIPHERAL
WAIT x
    0 x1
TITLE
    RM 100HZ
TITLE TO PERIPHERAL
WAIT x
    0 x1
TITLE
    CF 676.145105MZ
TITLE TO PERIPHERAL
WAIT x
    0 x1
CW FREQ
    676.045105M/u
TITLE
    ADJ A13 100KHZ
SEQUENCE
PAUSE
TITLE      051105 MZ
    CF 676.048105MZ
TITLE TO PERIPHERAL
WAIT x
    0 x1
```

*CW FREQ
676.048105M/u*

TITLE
ADJ A13 API1
SEQUENCE
PAUSE
TITLE
CF 676.007515MZ
TITLE TO PERIPHERAL
WAIT x
0 x1
CW FREQ
676.004515M/u
TITLE
ADJ A13 API2
SEQUENCE
PAUSE
TITLE
CF 676.003450MZ
TITLE TO PERIPHERAL
WAIT x
0 x1
CW FREQ
676.000450M/u
TITLE
ADJ A13 API3
SEQUENCE
PAUSE
TITLE
CF 676.003045MZ
TITLE TO PERIPHERAL
WAIT x
0 x1
CW FREQ
676.000045M/u
TITLE
ADJ A13 API4

4

Start Troubleshooting Here

The information in this chapter helps you:

- Identify the portion of the analyzer that is at fault.
- Locate the specific troubleshooting procedures to identify the assembly or peripheral at fault.

To identify the portion of the analyzer at fault, follow these procedures:

- Step 1. Initial Observations
- Step 2. Operator's Check
- Step 3. HP-IB Systems Check
- Step 4. Faulty Group Isolation

Assembly Replacement Sequence

The following steps show the sequence to replace an assembly in an HP 8753D network analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Having Your Analyzer Serviced

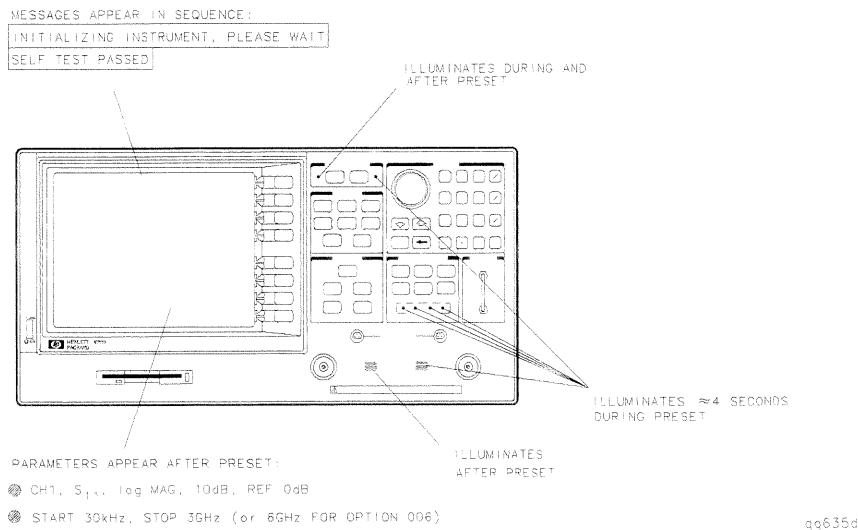
The HP 8753D has a one year on-site warranty, where available. If the analyzer should fail any of the following checks, call your local HP Sales and Service office. A customer engineer will be dispatched to service your analyzer on-site. If a customer engineer is not available in your area, follow the steps below to send your analyzer back to HP for repair.

1. Choose the nearest HP service center. (A table listing of Hewlett-Packard Sales and Service offices is provided at the end of this guide.)
2. Include a detailed description of any failed test and any error message.
3. Ship the analyzer, using the original or comparable anti-static packaging materials.

Step 1. Initial Observations

Initiate the Analyzer Self-Test

1. Disconnect all devices and peripherals from the analyzer.
2. Switch on the analyzer and press [PRESET].
3. Watch for the indications shown in Figure 4-1 to determine if the analyzer is operating correctly.



qg635d

Figure 4-1. Preset Sequence

If the Self-Test Failed

1. Check the AC line power to the analyzer.
2. Check the fuse (rating listed on rear panel, spare inside holder).
3. Check the line voltage setting (use small screwdriver to change).
4. If the problem persists, refer to "Step 4. Faulty Group Isolation."

Start Troubleshooting Here 4-3

Step 2. Operator's Check

This procedure verifies with 80% confidence that the analyzer is functioning properly.

Equipment

Short termination part of the HP 85031B calibration kit

Procedure

1. Connect a short to port 1 of the analyzer as shown in Figure 4-2.
2. Press **PRESET** **SYSTEM** **SERVICE MENU TESTS EXTERNAL TESTS EXECUTE TEST**.
3. Follow the prompts shown on the analyzer display then press **CONTINUE**.
4. Press **EXECUTE TEST**, follow the prompts shown on the analyzer display, and then press **CONTINUE**.

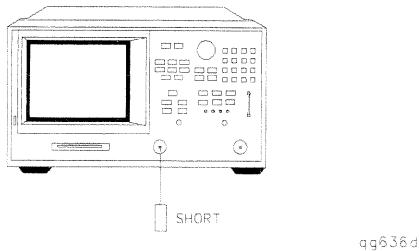


Figure 4-2. Operator's Check Setup

If the Operator's Check Failed

If the analyzer failed both checks, run the test again using a different short.

- If both tests pass, examine the original short for damage.
- If either test failed, go to step 2.

If the analyzer fails only one check, remove the bottom cover and check for loose or damaged semi-rigid cables in the test set assembly.

4-4 Start Troubleshooting Here

Step 3. HP-IB Systems Check

Check the analyzer's HP-IB functions with a *known working* passive peripheral (such as a plotter, printer, or disk drive).

1. Connect the peripheral to the analyzer using a *good* HP-IB cable..
2. Press **LOCAL SYSTEM CONTROLLER** to enable the analyzer to control the peripheral.
3. Then press **SET ADDRESSES** and the appropriate softkeys to verify that the device addresses will be recognized by the analyzer. The factory default addresses are:

Device	HP-IB Address
HP 8753D	16
Plotter port - HP-IB	5
Printer port - HP-IB	1
Disk (external)	0
Controller	21
Power meter - HP-IB	13

Note

You may use other addresses with two provisions:

- Each device must have its own address.
- The address set on each device must match the one recognized by the analyzer (and displayed).

Peripheral addresses are often set with a rear panel switch.
Refer to the manual of the peripheral to read or change its address.

If Using a Plotter or Printer

1. Ensure that the plotter or printer is set up correctly:
 - power is on
 - pens and paper loaded
 - pinch wheels are down
 - some plotters need to have P1 and P2 positions set
2. Press **[COPY]** and then **PLOT** or **PRINT MONOCHROME**.
 - If the result is a copy of the analyzer display, the printing/plotting features are functional in the analyzer. Continue with "Troubleshooting Systems with Multiple Peripherals", "Troubleshooting Systems with Controllers", or the "Step 4. Faulty Group Isolation" section in this chapter.
 - If the result is not a copy of the analyzer display, suspect the HP-IB function of the analyzer. Refer to Chapter 6, "Digital Control Troubleshooting."

If Using an External Disk Drive

1. Select the external disk drive. Press **[SAVE/RECALL] SELECT DISK EXTERNAL DISK**.
2. Verify that the address is set correctly. Press **[LOCAL] SET ADDRESSES ADDRESS:DISK**.
3. Ensure that the disk drive is set up correctly:
 - power is on
 - an initialized disk in the correct drive
 - correct disk unit number and volume number (press **[LOCAL]** to access the softkeys that display the numbers; default is 0 for both)
 - with hard disk (Winchester) drives, make sure the configuration switch is properly set (see drive manual)

4. Press **START** **1** **M/ μ** **SAVE/RECALL** **SAVE STATE**. Then press **PRESET** **SAVE/RECALL** **RECALL STATE**.

- If the resultant trace starts at 1 MHz, HP-IB is functional in the analyzer. Continue with "Troubleshooting Systems with Multiple Peripherals," "Troubleshooting Systems with Controllers", or the "Troubleshooting Systems with controllers," section in this chapter.
- If the resultant trace does not start at 1 MHz, suspect the HP-IB function of the analyzer: refer to Chapter 6, "Digital Control Troubleshooting."

Troubleshooting Systems with Multiple Peripherals

Connect any other system peripherals (but not a controller) to the analyzer one at a time and check their functionality. Any problems observed are in the peripherals, cables, or are address problems (see above).

Troubleshooting Systems with Controllers

Passing the preceding checks indicates that the analyzer's peripheral functions are normal. Therefore, if the analyzer has not been operating properly with an external controller, suspect the controller. Check the following:

- Compatibility, must be HP 9000 series 200/300. (See Chapter 1, "Service Equipment and Analyzer Options.")
- HP-IB interface hardware must be installed. (Refer to the manual, *Installing and Maintaining HP Basic/WS 6.2*, that comes with your HP Basic software.)
- Select code. (Refer to the manual, *Installing and Maintaining HP Basic/WS 6.2*, that comes with your HP Basic software.)
- I/O and HP-IB binaries loaded. (Refer to the manual, *Installing and Maintaining HP Basic/WS 6.2*, that comes with your HP Basic software.)
- HP-IB cables. (See "HP-IB Requirements" in the *HP 8753D Network Analyzer User's Guide*.)
- Programming syntax. (Refer to the *HP 8753D Network Analyzer Programmer's Guide*.)

If the analyzer appears to be operating unexpectedly but has not completely failed, go to "Step 4, Faulty Group Isolation."

Step 4. Faulty Group Isolation

Use the following procedures only if you have read the previous sections in this chapter and you think the problem is in the analyzer. These are simple procedures to verify the four functional groups in sequence, and determine which group is faulty.

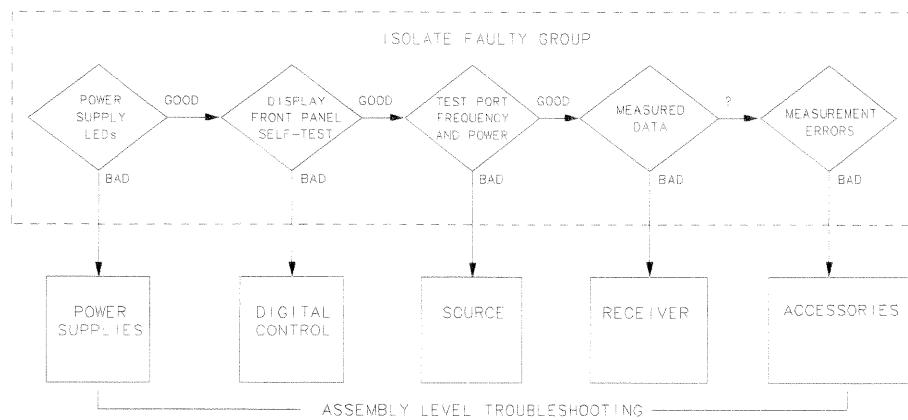
The four functional groups are:

- power supplies
- digital control
- source
- receiver

Descriptions of these groups are provided in Chapter 12, "Theory of Operation."

The checks in the following pages must be performed in the order presented. If one of the procedures fails, it is an indication that the problem is in the functional group checked. Go to the troubleshooting information for the indicated group, to isolate the problem to the defective assembly.

Figure 4-3 illustrates the troubleshooting organization.



sg645d

Figure 4-3. Troubleshooting Organization

4-8 Start Troubleshooting Here

Power Supply

Check the Rear Panel LEDs

Switch on the analyzer. Notice the condition of the two LEDs on the A15 preregulator at rear of the analyzer. (See Figure 4-4.)

- The upper (red) LED should be off.
- The lower (green) LED should be on.

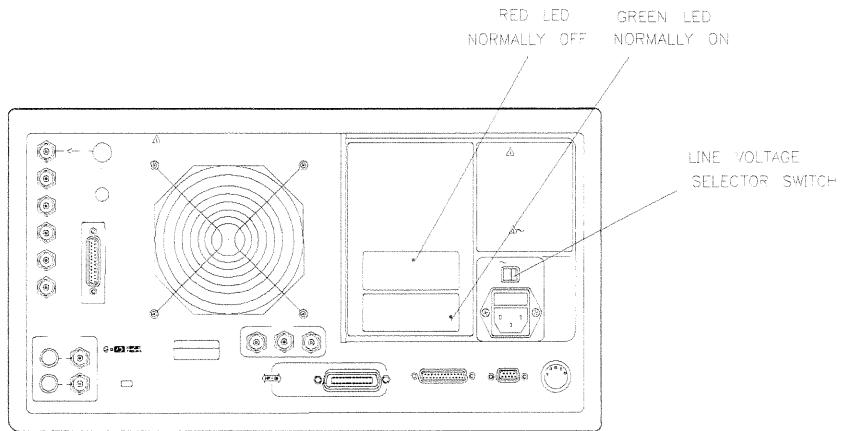


Figure 4-4. A15 Preregulator LEDs

Check the A8 Post Regulator LEDs

Remove the analyzer's top cover. Switch on the power. Inspect the green LEDs along the top edge of the A8 post-regulator assembly.

- All green LEDs should be on.
- The fan should be audible.

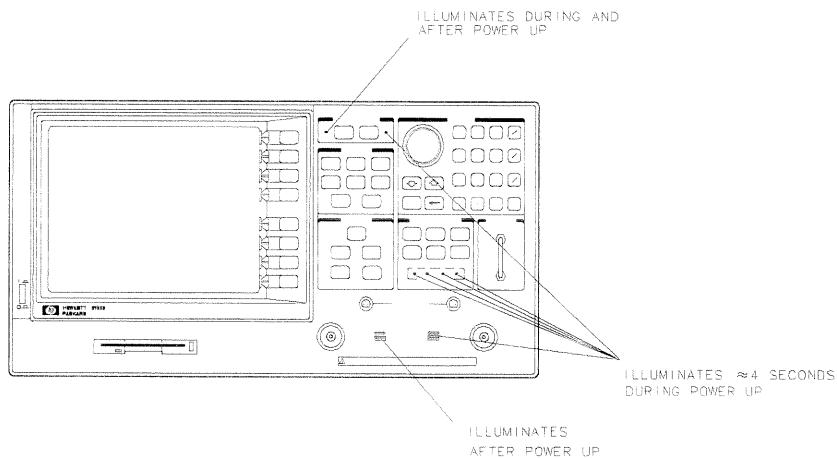
In case of difficulty, refer to Chapter 5, "Power Supply Troubleshooting."

Digital Control

Observe the Power Up Sequence

Switch the analyzer power off, then on. The following should take place within a few seconds:

- On the front panel observe the following:
 1. All six amber LEDs illuminate.
 2. The port 2 LED illuminates.
 3. The amber LEDs go off after a few seconds, except the CH 1 LED. At the same moment, the port 2 LED goes off and the port 1 LED illuminates.
(See Figure 4-5.)
- The display should come up bright and focused.
- Four red LEDs on the A9 CPU board should illuminate. They can be observed through a small opening in the rear panel.



sg639d

Figure 4-5. Front Panel Power Up Sequence

4-10 Start Troubleshooting Here

Verify Internal Tests Passed

1. Press **[PRESET]** **[SYSTEM]** **SERVICE MENU TESTS INTERNAL TESTS**

EXECUTE TEST. The display should indicate:

TEST

O ALL INT PASS

- If your display shows the above message, go to step 2. Otherwise, continue with this step.
 - If phase lock error messages are present, this test may stop without passing or failing. In this case, continue with the next procedure to check the source.
 - If you have unexpected results, or if the analyzer indicates a specific test failure, that internal test (and possibly others) have failed; the analyzer reports the first failure detected. Refer to Chapter 6, “Digital Control Troubleshooting.”
 - If the analyzer indicates failure but does not identify the test, press **①** to search for the failed test. Then refer to Chapter 6, “Digital Control Troubleshooting.” Likewise, if the response to front panel or HP-IB commands is unexpected, troubleshoot the digital control group.
2. Perform the Analog Bus test. Press **RETURN** **[19]** **[X1]** **EXECUTE TEST**.
- If this test fails, refer to Chapter 6, “Digital Control Troubleshooting.”
 - If this test passes, continue with the next procedure to check the source.

Source

Phase Lock Error Messages

The error messages listed below are usually indicative of a source failure or improper instrument configuration. (Ensure that the R channel input is receiving at least -35 dBm power). Continue with this procedure.

- NO IF FOUND: CHECK R INPUT LEVEL

The first IF was not detected during the pretune stage of phase lock.

- NO PHASE LOCK: CHECK R INPUT LEVEL

The first IF was detected at the pretune stage but phase lock could not be acquired thereafter.

- PHASE LOCK LOST

Phase-lock was acquired but then lost.

- PHASE LOCK CAL FAILED

An internal phase lock calibration routine is automatically executed at power-on, when pretune values drift, or when phase lock problems are detected. A problem spoiled a calibration attempt.

- POSSIBLE FALSE LOCK

The analyzer is achieving phase lock but possibly on the wrong harmonic comb tooth.

- SWEEP TIME TOO FAST

The fractional-N and the digital IF circuits have lost synchronization.

Check Source Output Power

1. Connect the equipment as shown in Figure 4-6.

4-12 Start Troubleshooting Here

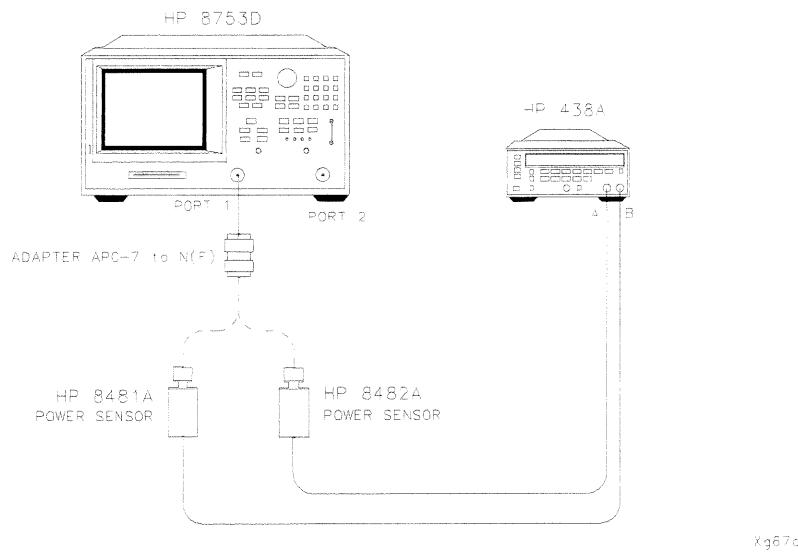


Figure 4-6. Equipment Setup for Source Power Check

2. Zero and calibrate the power meter. Press [PRESET] on the analyzer to initialize the instrument.
3. On the analyzer, press [MENU] CW FREQ [300] [k/m] to output a CW 300 kHz signal. The power meter should read approximately 0 dBm.
4. Press [16] [M/ μ] to change the CW frequency to 16 MHz. The power output power should remain approximately 0 dBm throughout the analyzers's frequency range. Repeat this step at 1 and 3 GHz. (For Option 006 include an additional check at 6 GHz.)

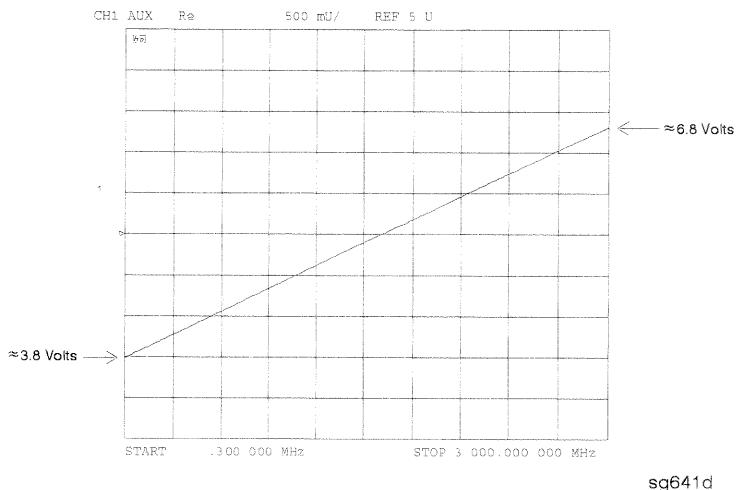
If any incorrect power levels are measured, refer to Chapter 7, "Source Troubleshooting."

No Oscilloscope or Power Meter? Try the ABUS

Monitor ABUS node 16.

1. Press **PRESET** **START** **300** **k/m** **STOP** **3** **G/n** **SYSTEM** **SERVICE MENU**
ANALOG BUS ON.
2. **MEAS** **ANALOG IN Aux Input** **[16]** **X1**.
3. **FORMAT** **MORE REAL** **[SCALE REF]** **AUTOSCALE**.

The display should resemble Figure 4-7.



sg641d

Figure 4-7. ABUS Node 16: 1V/GHz

If any of the above procedures provide unexpected results, or if error messages are present, refer to Chapter 7, "Source Troubleshooting."

4.14 Start Troubleshooting Here

Receiver

Observe the A and B Input Traces

1. Connect the equipment as shown in Figure 4-8 below. (The thru cable is HP part number 8120-4779.)

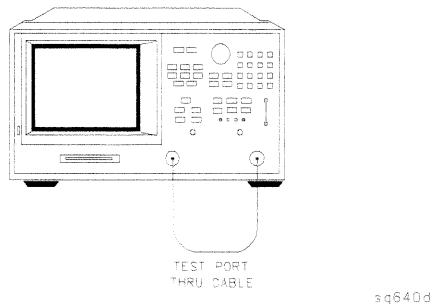


Figure 4-8. Equipment Setup

2. Press [PRESET] [MEAS] INPUT PORTS A TEST PORT 2 [SCALE REF]
AUTO SCALE .
3. Observe the measurement trace displayed by the A input. The trace should have about the same flatness as the trace in Figure 4-9.
4. Press [MEAS] INPUT PORTS TEST PORT 1 B .
5. Observe the measurement trace displayed by the B input. The trace should have about the same flatness as the trace in Figure 4-9.

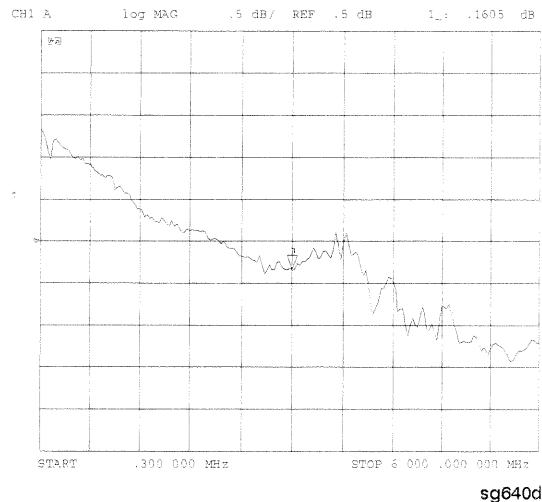


Figure 4-9. Typical Measurement Trace

If the source is working, but the A or B input traces appear to be in error, refer to Chapter 8, "Receiver Troubleshooting."

The following symptoms may also indicate receiver failure.

Receiver Error Messages

- CAUTION: OVERLOAD ON INPUT A; POWER REDUCED
- CAUTION: OVERLOAD ON INPUT B; POWER REDUCED
- CAUTION: OVERLOAD ON INPUT R; POWER REDUCED

The error messages above indicate that you have exceeded approximately +14 dBm at one of the test ports. The RF output power is automatically reduced to -85 dBm. The annotation P↓ appears in the left margin of the display to indicate that the power trip function has been activated. When this occurs, press **[MENU] POWER** and enter a lower power level. Press **SOURCE PWR ON** to switch on the power again.

4-16 Start Troubleshooting Here

Faulty Data

Any trace data that appears to be below the noise floor of the analyzer (-100 dBm) is indicative of a receiver failure.

Accessories

If the analyzer has passed all of the above checks but is still making incorrect measurements, suspect the system accessories. Accessories such as RF or interconnect cables, calibration or verification kit devices, and adapters can all induce system problems.

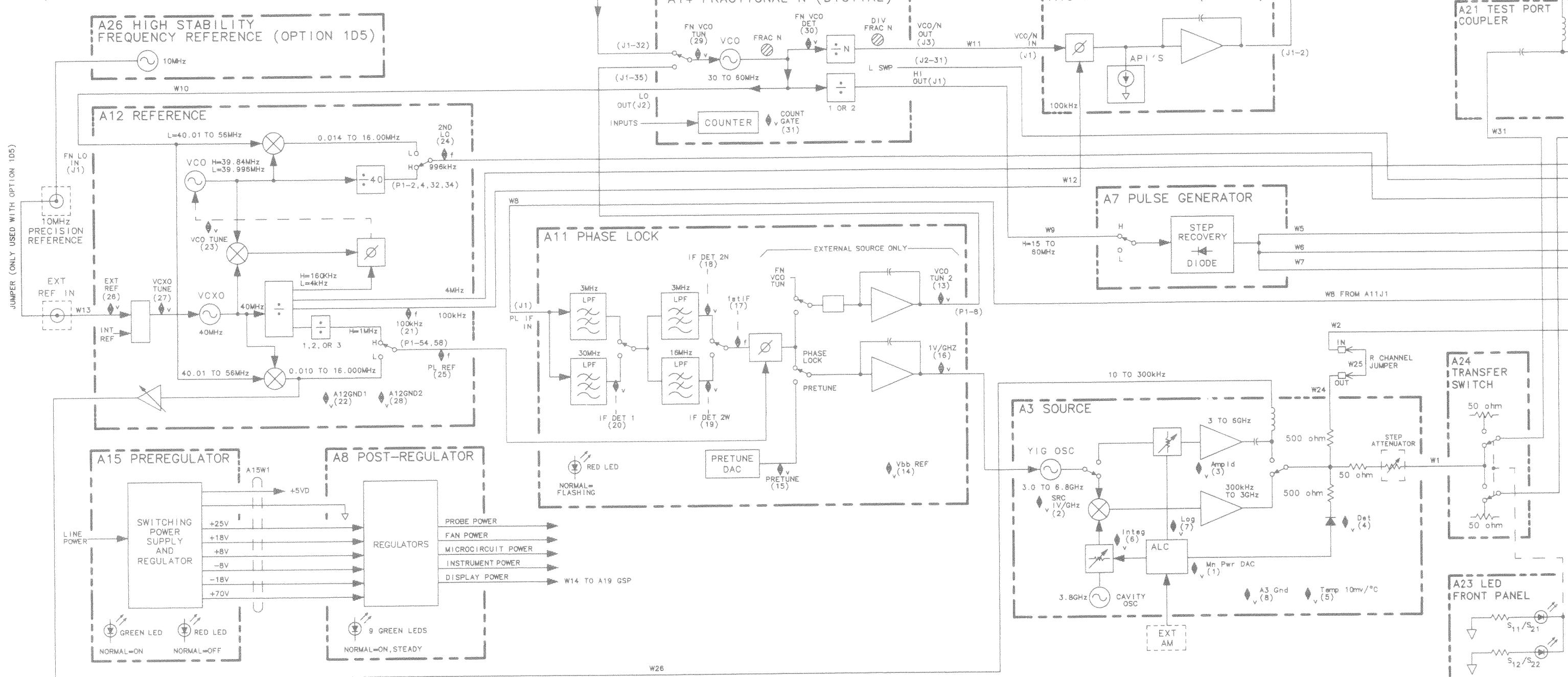
Reconfigure the system as it is normally used and reconfirm the problem. Continue with Chapter 9, “Accessories Troubleshooting.”

Accessories Error Messages

- **POWER PROBE SHUT DOWN!**

The biasing supplies to a front panel powered device (like a probe or millimeter module) are shut down due to excessive current draw. Troubleshoot the device.

HP 8753D OVERALL BLOCK DIAGRAM
(INCLUDES OPTIONS 006 & 1D5)



sg615d

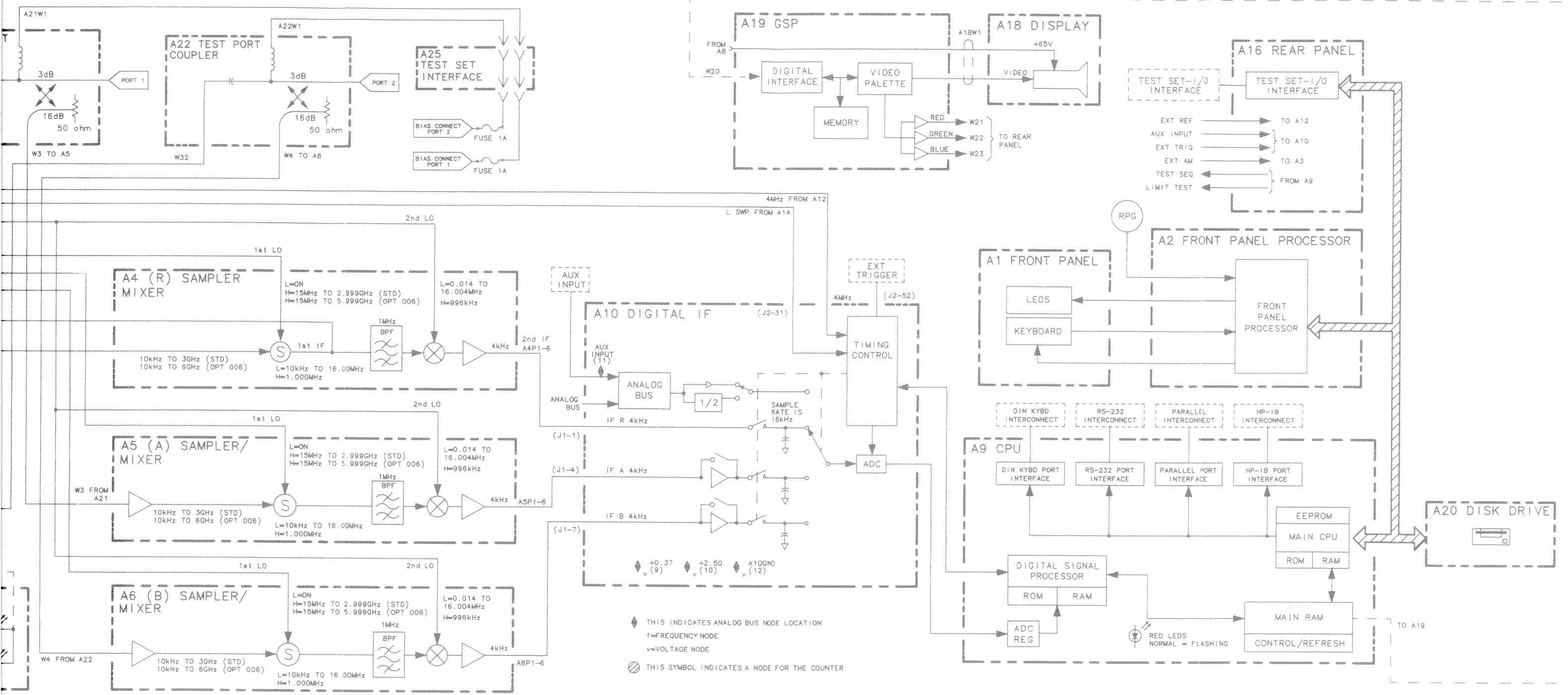


Figure 4-10. HP 8753D OVERALL BLOCK DIAGRAM

5

Power Supply Troubleshooting

Use this procedure only if you have read Chapter 4, “Start Troubleshooting Here.” Follow the procedures in the order given, unless:

- an error message appears on the display, refer to “Error Messages” near the end of this chapter.
- the fan is not working, refer to “Fan Troubleshooting” in this chapter.

The power supply group assemblies consist of the following:

- A8 post regulator
- A15 preregulator

All assemblies, however, are related to the power supply group because power is supplied to each assembly.

Assembly Replacement Sequence

The following steps show the sequence to replace an assembly in an HP 8753D network analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Simplified Block Diagram

Figure 5-1 shows the power supply group in simplified block diagram form. Refer to the detailed block diagram of the power supply (Figure 5-8) located at the end of this chapter to see voltage lines and specific connector pin numbers.

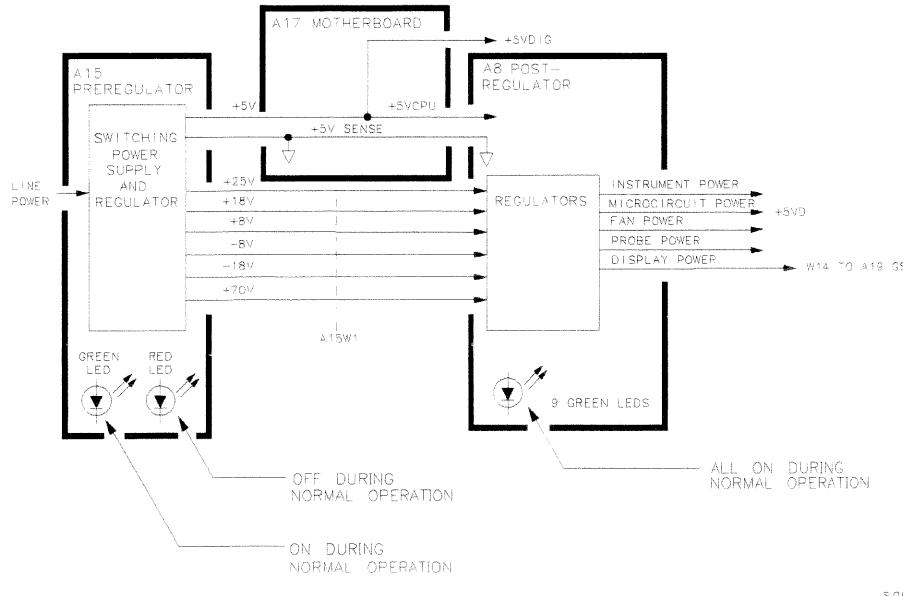


Figure 5-1. Power Supply Group Simplified Block Diagram

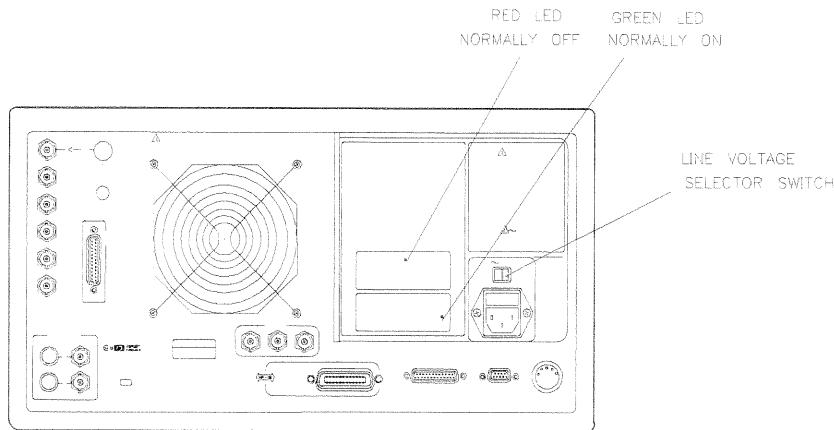
Start Here

Check the Green LED and Red LED on A15

Switch on the analyzer and look at the rear panel of the analyzer. Check the two power supply diagnostic LEDs on the A15 preregulator casting by looking through the holes located to the left of the line voltage selector switch. (See Figure 5-2.)

During normal operation, the bottom (green) LED is on and the top (red) LED is off. If these LEDs are normal, then A15 is 95% verified. Continue to "Check the green LEDs on A8."

- If the green LED is not on steadily, refer to "If the Green LED of the A15 Is not ON Steadily" in this procedure.
- If the red LED is on or flashing, refer to "If the Red LED of the A15 is ON" in this procedure.



sg637d

Figure 5-2. Location of A15 Diagnostic LEDs

5-4 Power Supply Troubleshooting

Check the Green LEDs on A8

Remove the top cover of the analyzer and locate the A8 post regulator; use the location diagram under the top cover if necessary. Check to see if the green LEDs on the top edge of A8 are all on. There are nine green LEDs (one is not visible without removing the PC board stabilizer).

- If all of the green LEDs on the top edge of A8 are on, there is a 95% confidence level that the power supply is verified. To confirm the last 5% uncertainty of the power supply, refer to “Measure the Post Regulator Voltages” (next).
- If any LED on the A8 post regulator is off or flashing, refer to “If the Green LEDs of the A8 are not All ON” in this procedure.

Measure the Post Regulator Voltages

Measure the DC voltages on the test points of A8 with a voltmeter. Refer to Figure 5-3 for test point locations and Table 5-1 for supply voltages and limits.

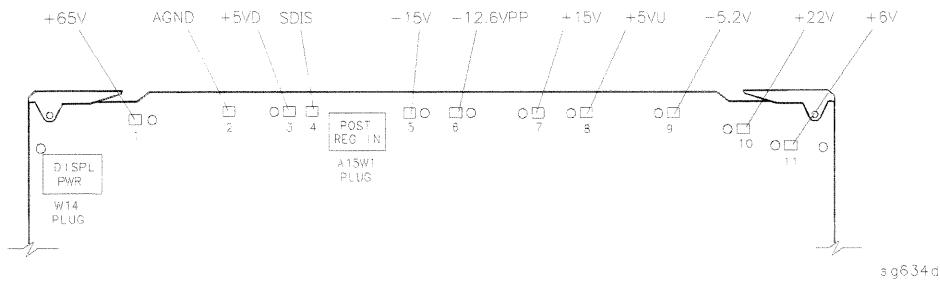


Figure 5-3. A8 Post Regulator Test Point Locations

Table 5-1. A8 Post Regulator Test Point Voltages

TP	Supply	Range
1	+65 V	+64.6 to +65.4
2	AGND	n/a
3	+5 VD	+4.9 to +5.3
4	SDIS	n/a
5	-15 V	-14.4 to -15.6
6	-12.6 VPP (probe power)	-12.1 to -12.8
7	+15 V	+14.5 to +15.5
8	-5 VU	+5.05 to +5.35
9	-5.2 V	-5.0 to -5.4
10	+22 V	+21.3 to +22.7
11	+6 V	+5.8 to +6.2

5-6 Power Supply Troubleshooting

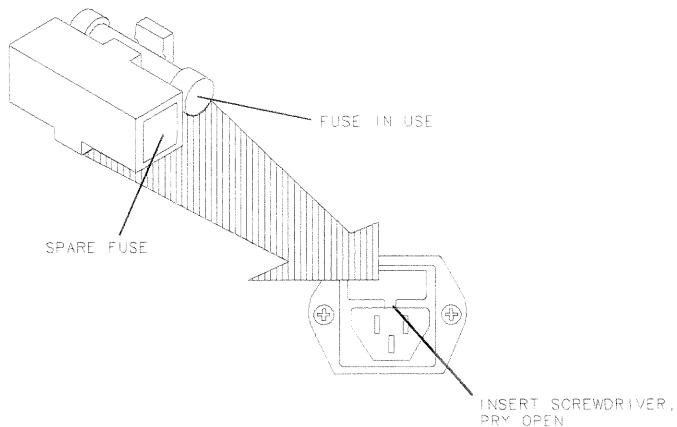
If the Green LED of the A15 Is not ON Steadily

If the green LED is not on steadily, the line voltage is not enough to power the analyzer.

Check the Line Voltage, Selector Switch, and Fuse

Check the main power line cord, line fuse, line selector switch setting, and actual line voltage to see that they are all correct. Figure 5-4 shows how to remove the line fuse, using a small flat-blade screwdriver to pry out the fuse holder. Figure 5-2 shows the location of the line voltage selector switch. Use a small flat-blade screwdriver to select the correct switch position.

If the A15 green LED is still not on steadily, replace A15.



49652d

Figure 5-4. Removing the Line Fuse

If the Red LED of the A15 is ON

If the red LED is on or flashing, the power supply is shutting down. Use the following procedures to determine which assembly is causing the problem.

Check the A8 Post Regulator

1. Switch off the analyzer.
2. Disconnect the cable A15W1 from the A8 post regulator. (See Figure 5-5.)
3. Switch on the analyzer and observe the red LED on A15.
 - If the red LED goes out, the problem is probably the A8 post regulator. Continue to "Verify the A15 Preregulator" to first verify that the inputs to A8 are correct.
 - If the red LED is still on, the problem is probably the A15 preregulator, or one of the assemblies obtaining power from it. Continue with "Check for a Faulty Assembly."

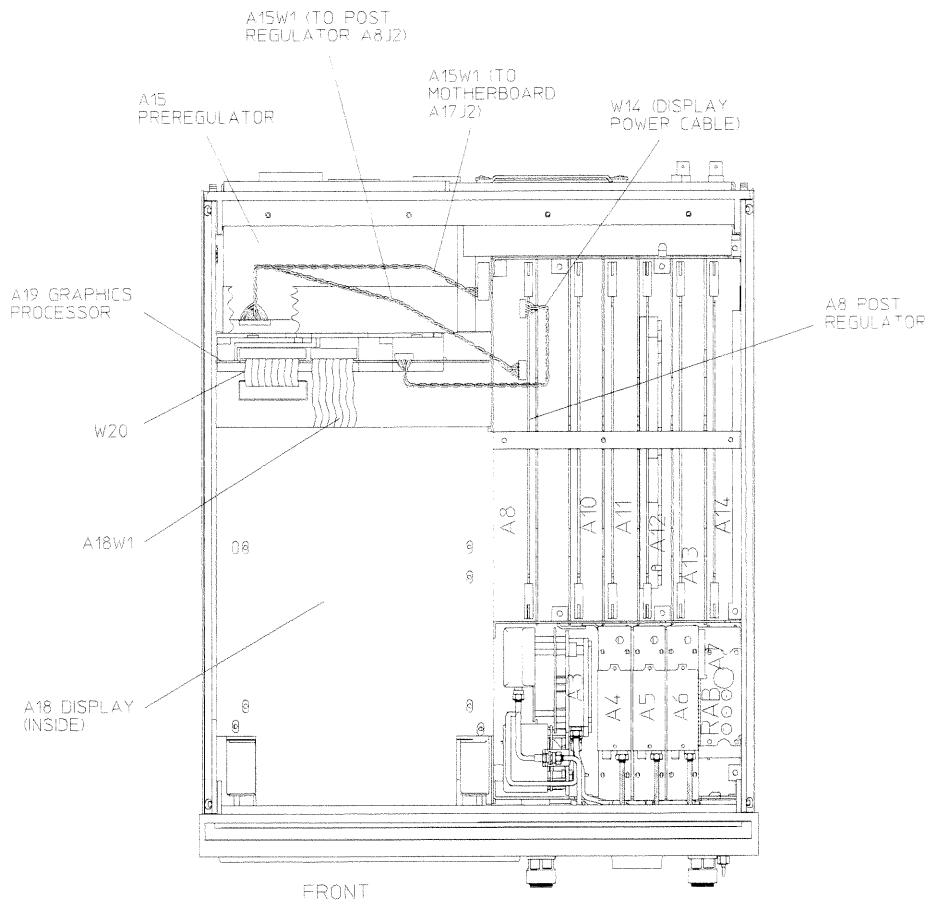


Figure 5-5. Power Supply Cable Locations

Verify the A15 Preregulator

Verify that the A15 preregulator is supplying the correct voltages to the A8 post regulator. Use a voltmeter with a small probe to measure the output voltages of A15W1's plug. Refer to Table 5-2 and Figure 5-6.

- If the voltages are not within tolerance, replace A15.
 - If the voltages are within tolerance, A15 is verified. Continue to “Check for a Faulty Assembly.”

Table 5-2. Output Voltages

Pin	A15W1P1 (Disconnected) Voltages	A8J2 (Connected) Voltages	A15 Preregulator Mnemonic
1,2	+125 to +100	+68 to +72	+70 V
3,4	+22.4 to +33.6	+17.0 to +18.4	+18 V
5,6	-22.4 to -33.6	-17.0 to -18.4	-18 V
7	N/C	N/C	N/C
8	-9.4 to +14	+7.4 to +8.0	+8 V
9,10	-9.4 to -14	-6.7 to -7.3	-8 V
11	+32 to +48	+24.6 to +26.6	+25 V
12	N/C	N/C	N/C

NOTE: The +5 VD supply must be loaded by one or more assemblies at all times, or the other voltages will not be correct. It connects to the motherboard connector A17J3 Pin 4.

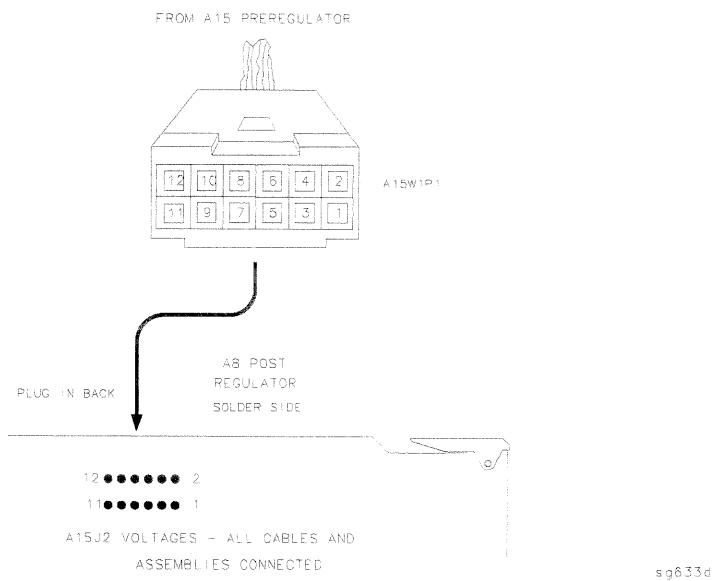


Figure 5-6. A15W1 Plug Detail

5-10 Power Supply Troubleshooting

Check for a Faulty Assembly

This procedure checks for a faulty assembly that might be shutting down the A15 preregulator via one of the following lines (also refer to Figure 5-1):

- A15W1 connecting to the A8 post regulator
- the +5VCPU line through the motherboard
- the +5VDIG line through the motherboard

Do the following:

1. Switch off the analyzer.
2. Ensure that A15W1 is reconnected to A8. (Refer to Figure 5-5.)
3. Remove or disconnect the assemblies listed in Table 5-3 one at a time and in the order shown. The assemblies are sorted from most to least accessible. Table 5-3 also lists any associated assemblies that are supplied by the assembly that is being removed. After each assembly is removed or disconnected switch on the analyzer and observe the red LED on A15.

Note

- *Always switch off the analyzer before removing or disconnecting assemblies.*
 - When extensive disassembly is required, refer to Chapter 14, “Assembly Replacement and Post-Repair Procedures.”
 - Refer to Chapter 13, “Replaceable Parts,” to identify specific cables and assemblies that are not shown in this chapter.
-

- If the red LED goes out, the particular assembly (or one receiving power from it) that allows it to go out is faulty.
- If the red LED is still on after you have checked all of the assemblies listed in Table 5-3, continue to “Check the Operating Temperature.”

Table 5-3. Recommended Order for Removal/Disconnection

Assembly To Remove	Removal or Disconnection Method	Other Assemblies that Receive Power from the Removed Assembly
1. A19 Graphics Processor	Disconnect W14	A18 Display
2. A14 Frac N Digital	Remove from Card Cage	None
3. A9 CPU	Disconnect W36	A20 Disk Drive
4. A16 Rear Panel Interface	Disconnect W27	A25 Test Set Interface A24 Transfer Switch A23 LED Front Panel
5. A2 Front Panel Interface	Disconnect W17	A1 Front Panel Keyboard

5.12 Power Supply Troubleshooting

Check the Operating Temperature

The temperature sensing circuitry inside the A15 preregulator may be shutting down the supply. Make sure the temperature of the open air operating environment does not exceed 55 °C (131 °F), and that the analyzer fan is operating.

- If the fan does not seem to be operating correctly, refer to “Fan Troubleshooting” at the end of this procedure.
- If there does not appear to be a temperature problem, it is likely that A15 is faulty.

Inspect the Motherboard

If the red LED is still on after replacement or repair of A15, switch off the analyzer and inspect the motherboard for solder bridges, and other noticeable defects. Use an ohmmeter to check for shorts. The +5VD, +5VCPU, or +5VDSENSE lines may be bad. Refer to the block diagram (Figure 5-8) at the end of this chapter and troubleshoot these suspected power supply lines on the A17 motherboard.

If the Green LEDs of the A8 are not All ON

The green LEDs along the top edge of the A8 post regulator are normally on.

Flashing LEDs on A8 indicate that the shutdown circuitry on the A8 post regulator is protecting power supplies from overcurrent conditions by repeatedly shutting them down. This may be caused by supply loading on A8 or on any other assembly in the analyzer.

Remove A8, Maintain A15W1 Cable Connection

1. Switch off the analyzer.
2. Remove A8 from its motherboard connector, but keep the A15W1 cable connected to A8.
3. Remove the display power cable W14. (See Figure 5-5.)
4. Short A8TP2 (AGND) (see Figure 5-3) to chassis ground with a clip lead.
5. Switch on the analyzer and observe the green LEDs on A8.
 - If any green LEDs other than +5VD are still off or flashing, continue to "Check the A8 Fuses and Voltages."
 - If all LEDs are now on steadily except for the +5VD LED, the A15 preregulator and A8 post regulator are working properly and the trouble is excessive loading somewhere after the motherboard connections at A8. Continue to "Remove the Assemblies."

Check the A8 Fuses and Voltages

Check the fuses along the top edge of A8. If any A8 fuse has burned out, replace it. If it burns out again when power is applied to the analyzer, A8 or A15 is faulty. Determine which assembly has failed as follows.

1. Remove the A15W1 cable at A8. (See Figure 5-5.)
2. Measure the voltages at A15W1P1 (see Figure 5-6) with a voltmeter having a small probe.
3. Compare the measured voltages with those in Table 5-2.
 - If the voltages are within tolerance, replace A8.
 - If the voltages are not within tolerance, replace A15.

If the green LEDs are now on, the A15 preregulator and A8 post regulator are working properly and the trouble is excessive loading somewhere after the motherboard connections at A8. Continue to “Remove the Assemblies.”

Remove the Assemblies

1. Switch off the analyzer.
2. Install A8. Remove the jumper from A8TP2 (AGND) to chassis ground.
3. Remove or disconnect all the assemblies listed below. (See Figure 5-5.)
Always switch off the analyzer before removing or disconnecting an assembly.
 - A10 digital IF
 - A11 phase lock
 - A12 reference
 - A13 fractional-N analog
 - A14 fractional-N digital
 - A19 graphics processor (disconnect W14, A18W1, and W20)
4. Switch on the analyzer and observe the green LEDs on A8.
 - If any of the green LEDs are off or flashing, it is not likely that any of the assemblies listed above is causing the problem. Continue to “Briefly Disable the Shutdown Circuitry.”
 - If all green LEDs are now on, one or more of the above assemblies may be faulty. Continue to next step.
5. Switch off the analyzer.
6. Reconnect W14 and W20 to A19.
7. Switch on the analyzer and observe the LEDs.
 - If the LEDs are off or blinking, replace the A19 assembly.
 - If the LEDs are still on, continue to next step.
8. Switch off the analyzer.
9. Reconnect A18W1 to the A19 assembly.
10. Switch on the analyzer and observe the LEDs.
 - If the LEDs are off, replace the A18 display.
 - If the LEDs are still on, continue with the next step.
11. Switch off the analyzer.

12. Reinstall each assembly one at a time. Switch on the analyzer after each assembly is installed. The assembly that causes the green LEDs to go off or flash could be faulty.

Note	It is possible, however, that this condition is caused by the A8 post regulator not supplying enough current. To check this, reinstall the assemblies in a different order to change the loading. If the same assembly appears to be faulty, replace that assembly. If a different assembly appears faulty, A8 is most likely faulty (unless both of the other assemblies are faulty).
-------------	--

Briefly Disable the Shutdown Circuitry

In this step, you shutdown the protective circuitry is disabled for a short time, and the supplies are forced on (including shorted supplies) with a 100% duty cycle.

Caution	Damage to components or to circuit traces may occur if A8TP4 (SDIS) is shorted to chassis ground for more than a few seconds while supplies are shorted.
----------------	--

1. Connect A8TP4 (SDIS) to chassis ground with a jumper wire.
2. Switch on the analyzer and note the signal mnemonics and test points of any LEDs that are off. *Immediately remove the jumper wire.*
3. Refer to the block diagram (Figure 5-8) at the end of this chapter and do the following:
 - Note the mnemonics of any additional signals that may connect to any A8 test point that showed a fault in the previous step.
 - Cross reference all assemblies that use the power supplies whose A8 LEDs went out when A8TP4 (SDIS) was connected to chassis ground.

- Make a list of these assemblies.
- Delete the following assemblies from your list as they have already been verified earlier in this section.

A10 digital IF
A11 phase lock
A12 reference
A13 fractional-N analog
A14 fractional-N digital
A18 display
A19 graphics processor

4. Switch off the analyzer.
5. Of those assemblies that are left on the list, remove or disconnect them from the analyzer one at a time. Table 5-4 shows the best order in which to remove them, sorting them from most to least accessible. Table 5-4 also lists any associated assemblies that are supplied by the assembly that is being removed. After each assembly is removed or disconnected switch on the analyzer and observe the LEDs.

Note

- *Always switch off the analyzer before removing or disconnecting assemblies.*
 - When extensive disassembly is required, refer to Chapter 14, “Assembly Replacement and Post-Repair Procedures.”
 - Refer to Chapter 13, “Replaceable Parts,” to identify specific cables and assemblies that are not shown in this chapter.
-

- If all the LEDs light, the assembly (or one receiving power from it) that allows them to light is faulty.
- If the LEDs are still not on steadily, continue to “Inspect the Motherboard.”

Table 5-4. Recommended Order for Removal/Disconnection

Assembly To Remove	Removal or Disconnection Method	Other Assemblies that Receive Power from the Removed Assembly
1. A3 Source	Remove from Card Cage	None
2. A7 Pulse Generator	Remove from Card Cage	None
3. A4 R Sampler	Remove from Card Cage	None
4. A5 A Sampler	Remove from Card Cage	None
5. A6 B Sampler	Remove from Card Cage	None
6. A9 CPU	Disconnect W35 and W36	A20 Disk Drive
7. A2 Front Panel Interface	Disconnect W17	A1 Front Panel Keyboard
8. A16 Rear Panel Interface	Disconnect W27	A25 Test Set Interface A24 Transfer Switch A23 LED Front Panel

Inspect the Motherboard

Inspect the A17 motherboard for solder bridges and shorted traces. In particular, inspect the traces that carry the supplies whose LEDs faulted when A8TP4 (SDIS) was grounded earlier.

5-18 Power Supply Troubleshooting

Error Messages

Three error messages are associated with the power supplies functional group. They are shown here.

■ POWER SUPPLY SHUT DOWN!

One or more supplies on the A8 post regulator assembly is shut down due to one of the following conditions: overcurrent, overvoltage, or undervoltage. Refer to "If the Red LED of the A15 is ON" earlier in this procedure.

■ POWER SUPPLY HOT

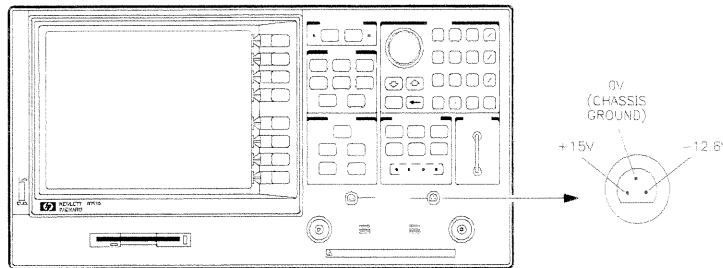
The temperature sensors on the A8 post regulator assembly detect an overtemperature condition. The regulated power supplies on A8 have been shut down.

Check the temperature of the operating environment; it should not be greater than +55 °C (131 °F). The fan should be operating and there should be at least 15 cm (6 in) spacing behind and all around the analyzer to allow for proper ventilation.

■ PROBE POWER SHUT DOWN!

The front panel RF probe biasing supplies are shut down due to excessive current draw. These supplies are +15VPP and -12.6VPP, both supplied by the A8 post regulator. +15VPP is derived from the +15 V supply. -12.6VPP is derived from the -12.6 V supply.

Refer to Figure 5-7 and carefully measure the power supply voltages at the front panel RF probe connectors.



sg638d

Figure 5-7. Front Panel Probe Power Connector Voltages

- If the correct voltages are present, troubleshoot the probe.
- If the voltages are not present, check the +15 V and -12.6 V green LEDs on A8.
 - If the LEDs are on, there is an open between the A8 assembly and the front panel probe power connectors. Put A8 onto an extender board and measure the voltages at the following pins:

A8P2 pins 6 and 36	-12.6 volts
A8P2 pins 4 and 34	+15 volts

- If the LEDs are off, continue with "Check the Fuses and Isolate A8."

Check the Fuses and Isolate A8

Check the fuses associated with each of these supplies near the A8 test points. If these fuses keep burning out, a short exists. Try isolating A8 by removing it from the motherboard connector, but keeping the cable A15W1 connected to A8J2. Connect a jumper wire from A8TP2 to chassis ground. If either the +15 V or -12.6 V fuse blows, or the associated green LEDs do not light, replace A8.

If the +15 V and -12.6 V green LEDs light, troubleshoot for a short between the motherboard connector pins XA8P2 pins 6 and 36 (-12.6 V) and the front panel probe power connectors. Also check between motherboard connector pins XA8P2 pins 4 and 34 (+15 V) and the front panel probe power connectors.

Fan Troubleshooting

Fan Speeds

The fan speed varies depending upon temperature. It is normal for the fan to be at high speed when the analyzer is just switched on, and then change to low speed when the analyzer is cooled.

Check the Fan Voltages

If the fan is dead, refer to the A8 post regulator block diagram (Figure 5-8) at the end of this chapter. The fan is driven by the +18 V and -18 V supplies coming from the A15 preregulator. Neither of these supplies is fused.

The -18 V supply is regulated on A8 in the fan drive block, and remains constant at approximately -14 volts. It connects to the A17 motherboard via pin 32 of the A8P1 connector.

The +18 V supply is regulated on A8 but changes the voltage to the fan, depending on airflow and temperature information. Its voltage ranges from approximately -1.0 volts to +14.7 volts, and connects to the A17 motherboard via pin 31 of the A8P1 connector.

Measure the voltages of these supplies while using an extender board to allow access to the PC board connector, A8P1.

Short A8TP3 to Ground

If there is no voltage at A8P1 pins 31 and 32, switch off the analyzer. Remove A8 from its motherboard connector (or extender board) but keep the cable A15W1 connected to A8. (See Figure 5-5.) Connect a jumper wire between A8TP3 and chassis ground. Switch on the analyzer.

- If all the green LEDs on the top edge of A8 light (except +5VD), replace the fan.
- If other green LEDs on A8 do not light, refer to "If the Green LEDs of the A8 are not All ON" earlier in this procedure.

Intermittent Problems

PRESET states that appear spontaneously (without pressing [PRESET]) typically signal a power supply or A9 CPU problem. Since the A9 CPU assembly is the easiest to substitute, do so. If the problem ceases, replace the A9. If the problem continues, replace the A15 preregulator assembly.

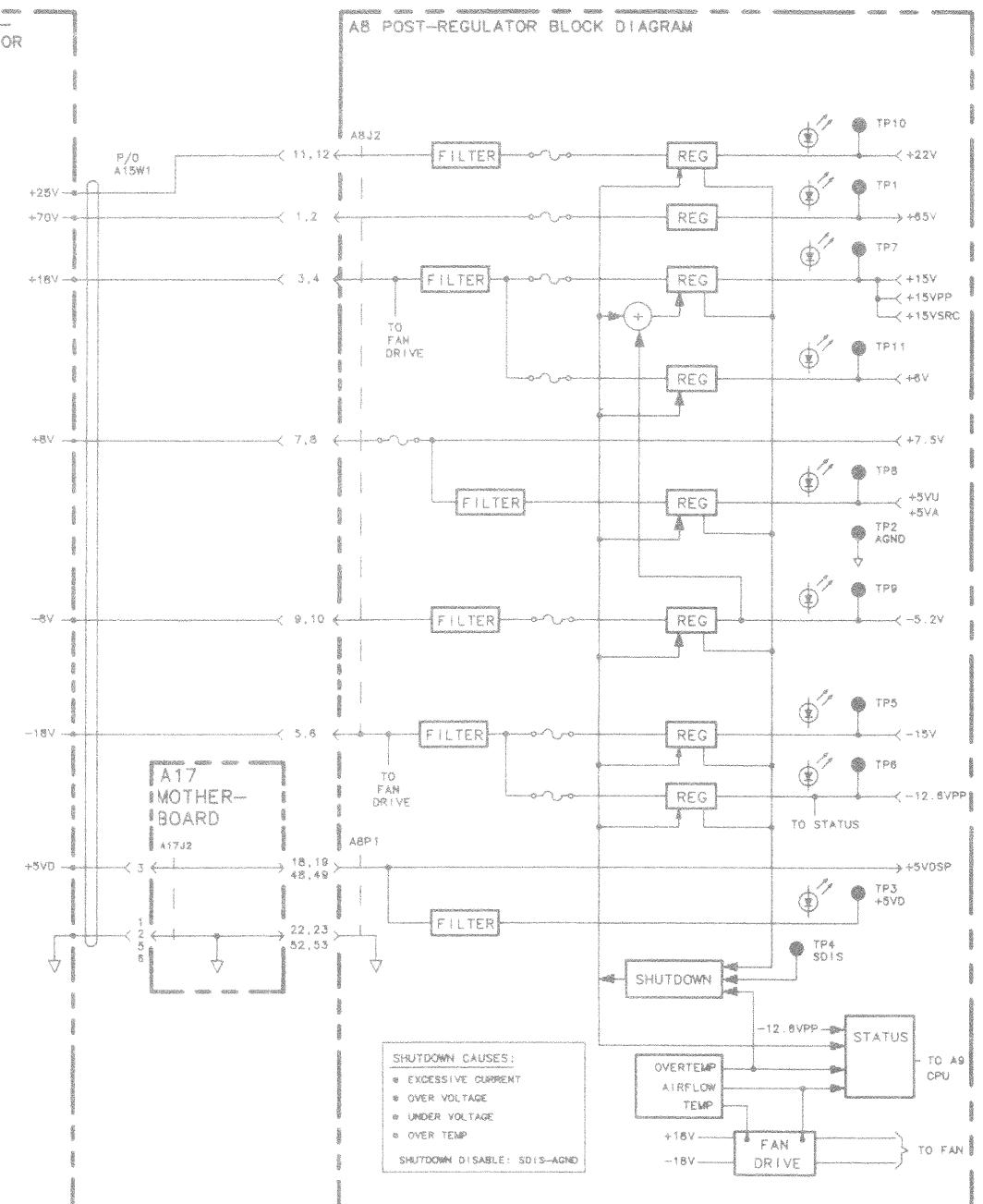
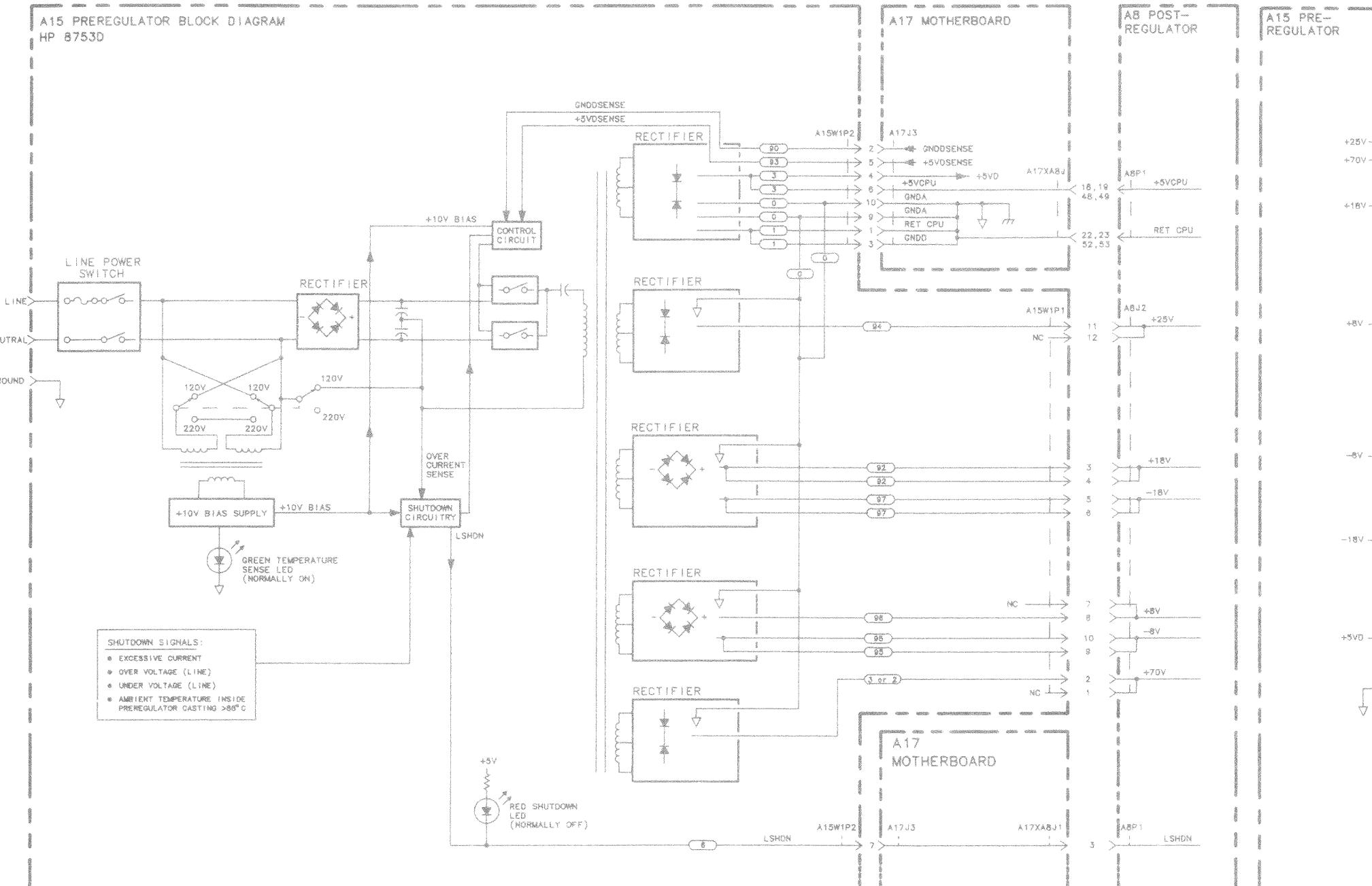


Figure 5-8. Power Supply Block Diagram

6

Digital Control Troubleshooting

Use this procedure only if you have read Chapter 4, “Start Troubleshooting Here.” Follow the procedures in the order given, unless instructed otherwise. If you suspect an HP-IB interface problem, refer to HP-IB Failures at the end of this chapter.

The digital control group assemblies consist of the following:

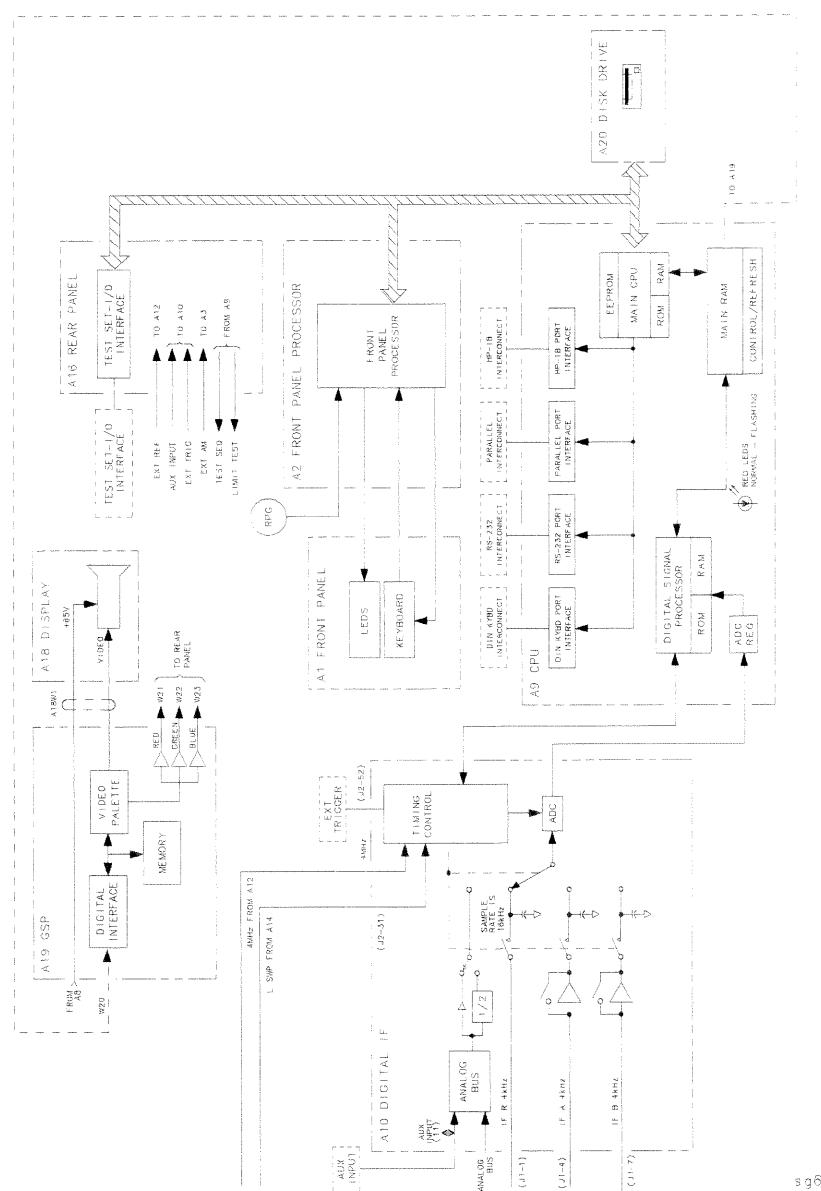
- A1 front panel keyboard
- A2 front panel interface
- A9 CPU
- A10 digital IF
- A16 rear panel
- A18 display
- A19 GSP

Assembly Replacement Sequence

The following steps show the sequence to replace an assembly in an HP 8753D network analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Digital Control Group Block Diagram



sg641d

Figure 6-1. Digital Control Group Block Diagram

Digital Control Troubleshooting 6-3

Check A9 CPU Operation

A9 CC Jumper Positions

The A9 CC jumper must be in the “NRM” (normal) position for these procedures. This is the position for normal operating conditions. To move the jumper to the “NRM” position, do the following:

1. Remove the power line cord from the analyzer.
2. Set the analyzer on its side.
3. Remove the two corner bumpers from the bottom of the instrument with a T-15 TORX screwdriver.
4. Loosen the captive screw on the bottom cover’s back edge.
5. Slide the cover toward the rear of the instrument.
6. Move the jumper to the NRM position as shown in Figure 6-2.
7. Replace the bottom cover, corner bumpers, and power cord.

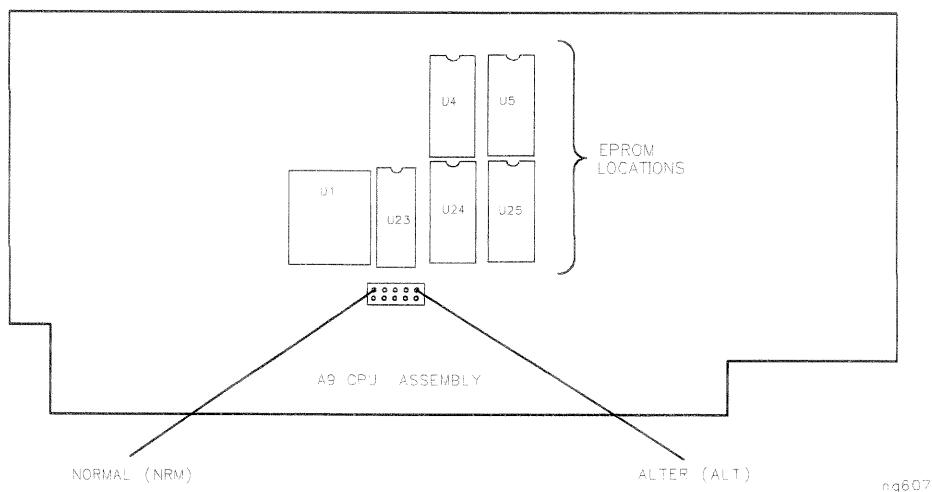


Figure 6-2. Jumper Positions on the A9 CPU

6-4 Digital Control Troubleshooting

Checking A9 CPU Red LED Patterns

The A9 CPU has four red LEDs that can be viewed through a small opening in the rear panel of the analyzer. (See Figure 6-3.)

1. Cycle the power

Cycle the power on the analyzer and observe the four red LEDs. All four LEDs should be on after power up.

If the four LEDs did not turn on, replace the A9 CPU after verifying the power supply.

2. Hold in the preset key

Press and hold down the **[PRESET]** key while observing the four LEDs on A9. The far right LED should be off. (See Figure 6-3.)

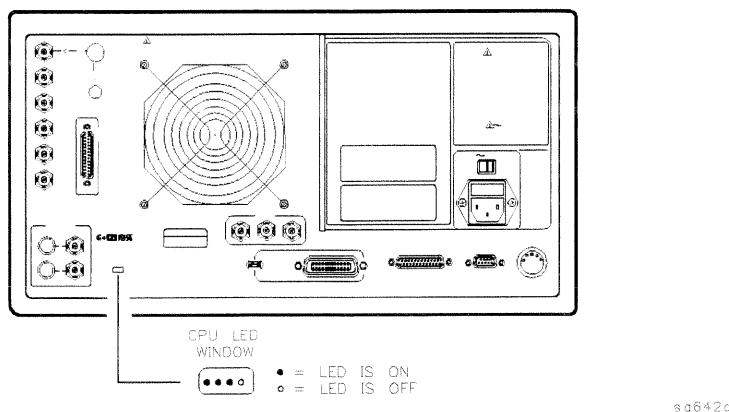


Figure 6-3. CPU LED Window on Rear Panel

3. Release the preset key

Release the **[PRESET]** key and watch for the *rapid* sequence shown below. Note that the far right LED always remains on.

- | | | | | |
|---|---|---|---|-----------------------------------|
| • | • | • | ○ | [PRESET] still held down |
| ○ | • | ○ | ● | [PRESET] released – Pattern 1 |
| • | • | ○ | ● | Pattern 2 |
| • | • | ● | ● | Pattern 3 |
| • | ○ | ○ | ● | Pattern 4 |
| • | • | ● | ● | Pattern 5 – two left LEDs flicker |

4. Observe and evaluate results

- If the above sequence is observed, and the far right LED remained on, go to “Check A19 GSP and A18 Display Operation.”
- If the right LED does not remain on, replace the A9 CPU assembly and repeat the three LED pattern checks.
- If the LEDs are held in any one of the patterns shown in Table 6-1, and have the corresponding error message, replace the A9 firmware ICs. (Firmware ICs are not separately replaceable. Replacement kits are listed in Chapter 13, “Replaceable Parts.”)

Table 6-1. LED Code and Pattern Versus Test Failed

LED Code Sum	Message Displayed	Faulty Component
• • • ○	ROM 1L FAIL	U24
• • • •	ROM 1M FAIL	U4
○ • • •	ROM 2L FAIL	U25
○ • • •	ROM 2M FAIL	U5

Check A19 GSP and A18 Display Operation

Cycle Power and Look at the Display

Switch the analyzer off, and then on. The display should be bright and focused with the annotation legible and intelligible.

- If the display is acceptable, go to “A1/A2 Front Panel Troubleshooting.”
- If the display is unacceptable, continue with the next step.

Perform Display Intensity and Focus Adjustments

In Chapter 3, “Adjustments and Correction Constants,” perform the “Display Intensity Adjustments.” If this does not resolve the problem, refer to “A19 GSP and A18 Display Troubleshooting.” located later in this chapter.

A1/A2 Front Panel Troubleshooting

Check Front Panel LEDs After Preset

1. Press **[PRESET]** on the analyzer.
2. Observe that all front panel LEDs turn on and, within five seconds after releasing **[PRESET]**, all but the CH1 LED turns off. Refer to Figure 6-4.
 - If all the front panel LEDs either stay on or off, there is a control problem between A9 and A1/A2. See “Inspect Cables,” located later in this chapter.
 - If, at the end of the turn on sequence, the channel 1 LED is not on and all HP-IB status LEDs are not off, continue with “Identify the Stuck Key.”

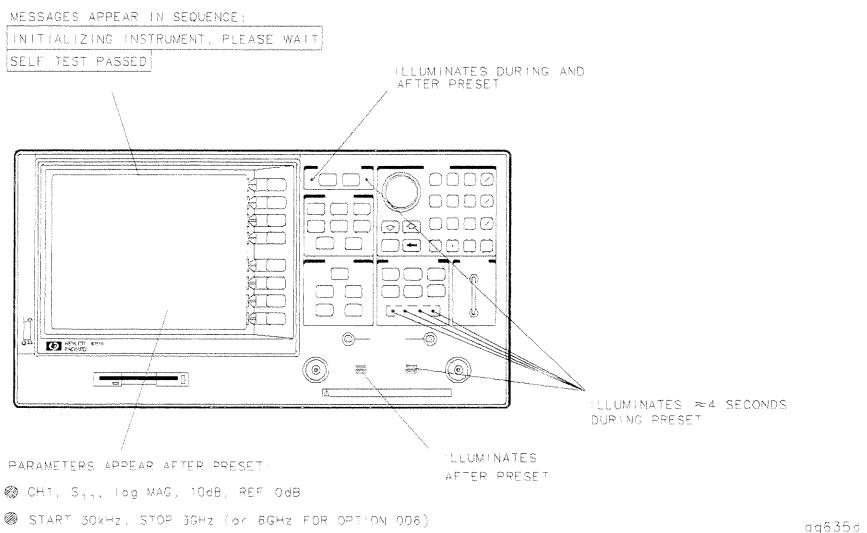


Figure 6-4. Preset Sequence

Identify the Stuck Key

Match the LED pattern with the patterns in Table 6-2. The LED pattern identifies the stuck key. Free the stuck key or replace the front panel part causing the problem.

6-8 Digital Control Troubleshooting

Table 6-2. Front Panel Key Codes

Decimal Number	LED Pattern						Key	Front Panel Block
	CHAN 1	CHAN 2	R	L	T	S		
0							CAL	Response
1						•	3	Entry
2				•			k/m	Entry
3				•	•		DISPLAY	Response
4			•				Avg	Response
5			•			•	2	Entry
6			•	•			1	Entry
7			•	•	•		softkey 3	Softkey
8		•					softkey 5	Softkey
9		•				•	9	Entry
10		•		•			G/n	Entry
11		•		•	•		CH 1	Active Channel
12		•	•				CH 2	Active Channel
13		•	•			•	8	Entry
14		•	•	•			7	Entry
15		•	•	•	•		softkey 1	Softkey
16	•						STOP	Stimulus
17	•					•	SAVE/RECALL	Instrument State
18	•					•	SEQ	Instrument State
19	•			•	•		MENU	Stimulus
20	•		•				START	Stimulus
21	•		•			•	COPY	Instrument State
22	•		•	•			SYSTEM	Instrument State
23	•		•	•	•		softkey 6	Softkey
24	•	•				•	SCALE REF	Response
25	•	•				•	6	Entry

Table 6-2. Front Panel Key Codes (continued)

Decimal Number	LED Pattern						Key	Front Panel Block
	CHAN 1	CHAN 2	R	L	T	S		
26			•			•		Entry
27			•	•		•		Response
28			•	•	•			Response
29			•	•	•			Entry
30			•	•	•	•		Entry
31			•	•	•	•	softkey 2	Softkey
32	•							Stimulus
33	•					•		Entry
34	•				•			Entry
35	•				•	•		Stimulus
36	•			•			softkey 8	Softkey
37	•			•		•		Entry
38	•			•	•			Instrument State
39	•			•	•	•	softkey 7	Softkey
40-47	Not used							
48	•	•						Entry
49	•	•				•		Entry
50	•	•			•			Entry
51	•	•			•	•		Response
52	•	•		•				Response
53	•	•		•		•		Entry
54	•	•		•	•			Entry
55	•	•		•	•	•	softkey 4	Softkey

Inspect Cables

Remove the front panel assembly and visually inspect the ribbon cable that connects the front panel to the motherboard. Also, inspect the interconnecting ribbon cable between A1 and A2. Make sure the cables are properly connected. Replace any bad cables.

6-10 Digital Control Troubleshooting

Test Using a Controller

If a controller is available, write a simple command to the analyzer. If the analyzer successfully executes the command, the problem is either the A2 front panel interface or W17 (A2 to motherboard ribbon cable) is faulty.

Run the Internal Diagnostic Tests

The analyzer incorporates 20 internal diagnostic tests. Most tests can be run as part of one or both major test sequences: all internal (test 0) and preset (test 1).

1. Press **SYSTEM** SERVICE MENU TESTS **0** **x1** EXECUTE TEST to perform all INT tests.
2. Then press **1** **x1** to see the results of the preset test. If either sequence fails, press the **↑** **↓** keys to find the first occurrence of a FAIL message for tests 2 through 20. See Table 6-3 for further troubleshooting information.

Table 6-3. Internal Diagnostic Test with Commentary

Test	Sequence*	Probable Failed Assemblies†; Comments and Troubleshooting Hints
0 All Int	--	--: Executes tests 3-11, 13-16, 20.
1 Preset	--	--: Executes tests 2-11, 14-16. Runs at power-on or preset.
2 ROM	P,AI	A9: Repeats on fail; refer to "Check A9 CPU Operation" in this chapter to replace ROM or A9.
3 CMOS RAM	P,AI	A9: Replace A9.
4 Main DRAM	P,AI	A9: Repeats on fail; replace A9.
5 DSP Wr/Rd	P,AI	A9: Replace A9.
6 DSP RAM	P,AI	A9: Replace A9.
7 DSP ALU	P,AI	A9: Replace A9.
8 DSP Intrpt	P,AI	A9/A10: Remove A10, rerun test. If fail, replace A9. If pass, replace A10.
9 DIF Control	P,AI	A9/A10: Most likely A9 assembly.
10 DIF Counter	P,AI	A10/A9/A12: Check analog bus node 17 for 1 MHz. If correct, A12 is verified; suspect A10.
11 DSP Control	P,AI	A10/A9: Most likely A10.
12 Fr Pan Wr/Rd	--	A2/A1/A9: Run test 23. If fail, replace A2. If pass, problem is on bus between A9 and A2 or on A9 assembly.
13 Rear Panel	AI	A16/A9: Disconnect A16, and check A9J2 pin 48 for 4 MHz clock signal. If OK, replace A16. If not, replace A9.
14 Post-reg	P,AI	A15/A8/Destination assembly: See Chapter 5, "Power Supply Troubleshooting."
15 Frac-N Cont	P,AI	A14: Replace A14.
16 Sweep Trig	P,AI	A14,A10: Most likely A14.
17 ADC Lin	--	A10: Replace A10.
18 ADC Ofs	--	A10: Replace A10.
19 ABUS Test	--	A10: Replace A10.
20 FN Count	AI	A14/A13/A10: Most likely A14 or A13, as previous tests check A10. See Chapter 7, "Source Troubleshooting."

* P = part of PRESET sequence; AI = part of ALL INTERNAL sequence.

† in decreasing order of probability.

6-12 Digital Control Troubleshooting

A19 GSP and A18 Display Troubleshooting

Measure Display Power Supply Voltages on A19

Measure the display power supply voltages on the A19 GSP assembly. Check pins 2, 4, and 6 on A19J5 for $+65 \pm 0.4$ V. (See Figure 6-5.) If the voltages are incorrect, continue with the next check. Otherwise, go to “Run Display Test 59” later in this chapter.

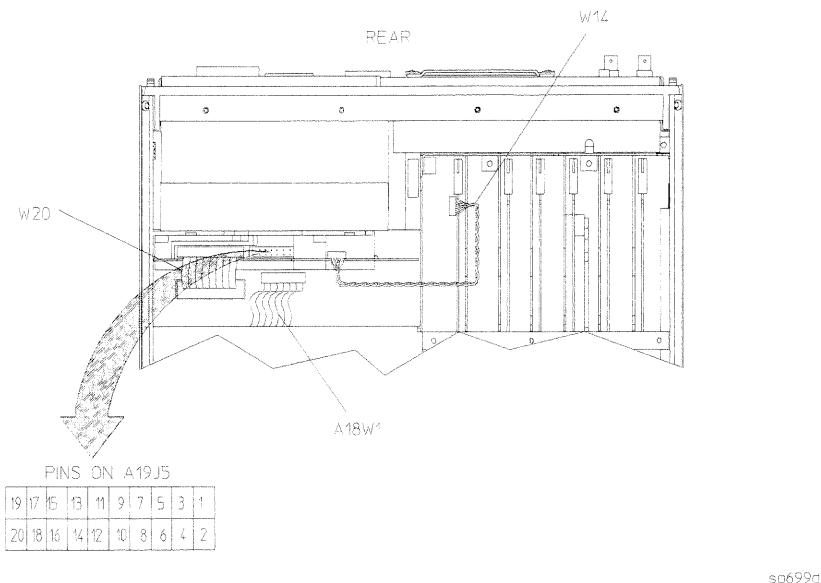


Figure 6-5. Pin Locations on A19J5

Measure Display Power Supply Voltages Entering A19

Measure the power supply voltages entering the A19 assembly coming from the A8 assembly. Check pins 1 and 2 on the connector of W14 for $+65 \pm 0.4$ V, and pin 6 for $+5.16 \pm 0.1$ V. (See Figure 6-6.)

- If the voltages are incorrect, refer to Chapter 5, “Power Supply Troubleshooting.”
- If the voltages are correct entering, but incorrect leaving the GSP assembly, replace the A19 GSP assembly.

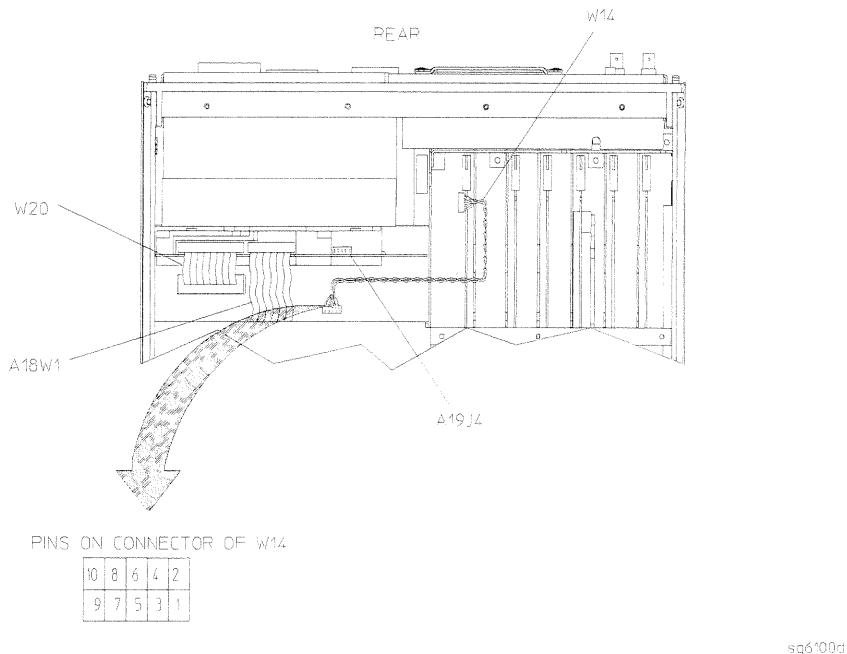


Figure 6-6. Pin Locations on Connector of W14

Run Display Test 59

1. On the analyzer, press [PRESET] [SYSTEM] SERVICE MENU (softkey 8) TESTS (softkey 1) DISPLAY TESTS (softkey 7). The CRT will display:
59 Disp/cpu com -ND-
2. Press EXECUTE TEST (softkey 8). The display will blank and the front panel LEDs will flash once. All of the LEDs will go off and the display will remain blank if the test passes. If any of the front panel LEDs remain on (except for the port LEDs), the analyzer failed the test.

If the analyzer passes the test, press [PRESET] and go to “Run Display Tests 60-65.” Otherwise, continue with the next check.

Inspect Ribbon Cable Repeat Display Test 59

Inspect the W20 (A9-A19) ribbon cable for a loose connection. Repeat “Run Display Tests 60-65.” If the test fails, a walking one pattern will be continuously transferred from the CPU, through the cable, to the GSP. Immediately go to the next check.

Perform Walking One Pattern

Disconnect the W20 (A9-A19) ribbon cable from A19J6. Use an oscilloscope to verify a walking one pattern is transferring from the A9 CPU through the cable. The walking one pattern (see Figure 6-7) is found on pins 3 through 10, and 13 through 20 on the connector of W20. (See Figure 6-8.)

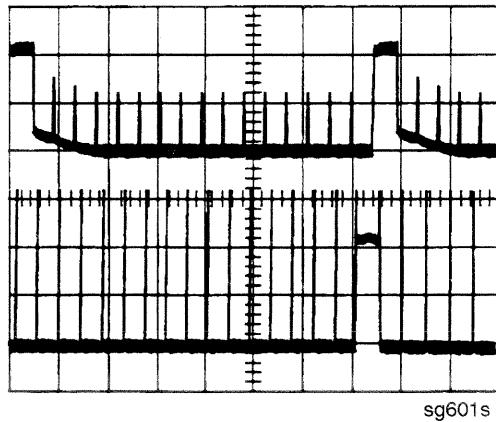
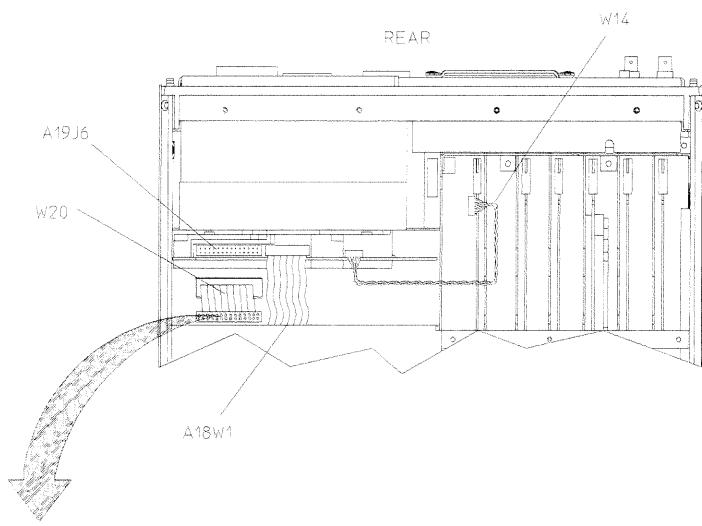


Figure 6-7. A9 CPU Walking One Pattern



PINS ON CONNECTOR OF W20																			
34	32	30	28	26	24	22	20	18	16	14	12	10	8	6	4	2			
33	31	29	27	25	23	21	19	17	15	13	11	9	7	5	3	1			

sg698d

Figure 6-8. Pin Locations on Connector of W20

If the signal is not present at the end of the cable, check for it at the A9 connector of the ribbon cable. If the signal is still not present, replace the A9 assembly.

6-16 Digital Control Troubleshooting

Run Display Tests 60-65

1. Press [PRESET] [SYSTEM] SERVICE MENU (softkey 8) TESTS (softkey 1) DISPLAY TESTS (softkey 7) [60] [X1].
2. Press EXECUTE TEST (softkey 8). The display will blank and the front panel LEDs will flash once. If the test passes, all the LEDs will go off and the display will remain blank.
3. Press [PRESET] and perform display tests 61 through 65 (substitute the next test number where [60] was used). Watch for the LEDs to go off and the display to blank except for test 65. Test 65 causes the display to dim rather than blank.
 - If any of the display tests fail, replace the A19 assembly.
 - If all of the following is true, replace the A18 display assembly.
 - CPU test passes the LED test.
 - GSP passes all of the internal display tests (59 through 65).
 - Power supply checks out.
 - Intensity, focus, and vertical adjustments fail to produce an acceptable image.

If the Fault is Intermittent

Repeat Test Function

If the failure is intermittent, do the following:

1. Press **SYSTEM SERVICE MENU TEST OPTIONS REPEAT ON** to turn on the repeat function.
2. Then press **RETURN TESTS**.
3. Select the test desired and press **EXECUTE TEST**.
4. Press any key to stop the function. The test repeat function is explained in Chapter 10, "Service Key Menus and Error Messages."

HP-IB Failures

If you have performed "Step 3. Troubleshooting HP-IB Systems" in Chapter 4, "Start Troubleshooting Here," and you suspect there is an HP-IB problem in the analyzer, perform the following test. It checks the internal communication path between the A9 CPU and the A16 rear panel. It does not check the HP-IB paths external to the instrument.

Press **SYSTEM SERVICE MENU TESTS [13] [x1] EXECUTE TEST**.

- If the analyzer fails the test, the problem is likely to be the A16 rear panel.
- If the analyzer passes the test, it indicates that the A9 CPU can communicate with the A16 rear panel with a 50% confidence level. There is a good chance that the A16 rear panel is working. This is because internal bus lines have been tested between the A9 CPU and A16, and HP-IB signal paths are not checked external to the analyzer.

7

Source Troubleshooting

Use this procedure only if you have read Chapter 4, “Start Troubleshooting Here.” This chapter is divided into two troubleshooting procedures for the following problems:

- Incorrect power levels: Perform the “Power” troubleshooting checks.
- Phase lock error: Perform the “Phase Lock Error” troubleshooting checks.

The source group assemblies consist of the following:

- A3 source
- A4 sampler/mixer
- A7 pulse generator
- A11 phase lock
- A12 reference
- A13 fractional-N (analog)
- A14 fractional-N (digital)

Assembly Replacement Sequence

The following steps show the sequence to replace an assembly in an HP 8753D Network Analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Before You Start Troubleshooting

Make sure all of the assemblies are firmly seated. Also make sure that input R has a signal of at least -35 dBm (about 0.01 Vp-p into 50 ohms) at all times to maintain phase lock.

Power

If the analyzer output power levels are incorrect but no phase lock error is present, perform the following checks in the order given:

1. Source Default Correction Constants (Test 44)

To run this test, press [PRESET] [SYSTEM] SERVICE MENU TESTS [44] [x1]

EXECUTE TEST. When complete, DONE should appear on the analyzer display. Use a power meter to verify that source power can be controlled and that the power level is approximately correct. If the source passes these checks, proceed with step 2. However, if FAIL appears on the analyzer display, or if the analyzer fails the checks, replace the source.

2. RF Output Power Correction Constants (Test 47)

Follow the instructions for this procedure given in Chapter 3, "Adjustments and Correction Constants." The procedure is complete when DONE appears on the analyzer display. Use a power meter to verify that power levels are now correct. If power levels are not correct, or if the analyzer fails the routine, proceed with step 3.

3. Sampler Magnitude and Phase Correction Constants (Test 53)

Follow the instructions for this procedure given in Chapter 3, "Adjustments and Correction Constants." The procedure is complete when DONE appears on the analyzer display. Next, repeat step 2. If the analyzer fails the routine in step 2, replace the source.

If the analyzer fails the routine in step 3, replace the source.

Phase Lock Error

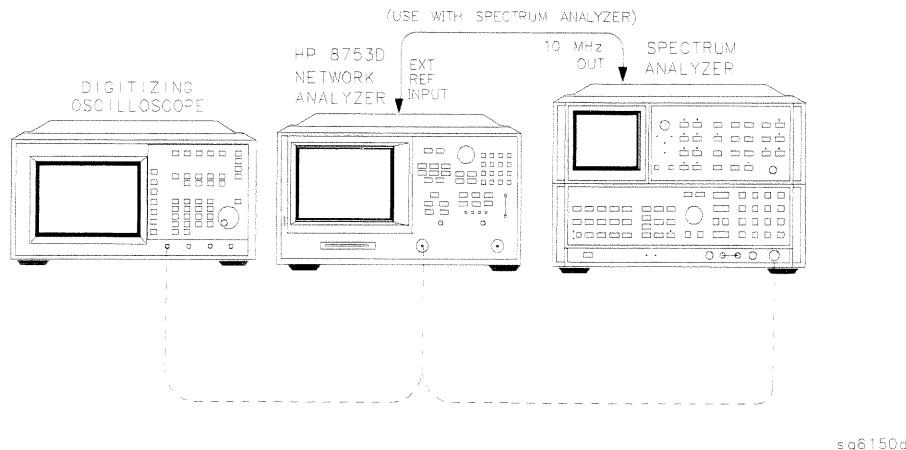


Figure 7-1. Basic Phase Lock Error Troubleshooting Equipment Setup

Troubleshooting tools include the assembly location diagram and phase lock diagnostic tools. The assembly location diagram is on the underside of the instrument top cover. The diagram shows major assembly locations and RF cable connections. The phase lock diagnostic tools are explained in the “Source Group Troubleshooting Appendix” and should be used to troubleshoot phase lock problems. The equipment setup shown in Figure 7-1 can be used throughout this chapter.

Phase Lock Loop Error Message Check

Phase lock error messages may appear as a result of incorrect pretune correction constants. To check this possibility, perform the pretune correction constants routine.

The four phase lock error messages, listed below, are described in the “Source Group Troubleshooting Appendix” at the end of this chapter.

- NO IF FOUND: CHECK R INPUT LEVEL
- NO PHASE LOCK: CHECK R INPUT LEVEL
- PHASE LOCK CAL FAILED

7-4 Source Troubleshooting

■ PHASE LOCK LOST

1. Make sure the A9 CC Jumper is in the ALTER position:
 - a. Remove the power line cord from the analyzer.
 - b. Set the analyzer on its side.
 - c. Remove the two corner bumpers from the bottom of the instrument with a T-15 TORX screwdriver.
 - d. Loosen the captive screw on the bottom cover's back edge.
 - e. Slide the cover toward the rear of the instrument.
 - f. Move the jumper to the ALT position as shown in Figure 7-2.
 - g. Replace the bottom cover, corner bumpers, and power cord.

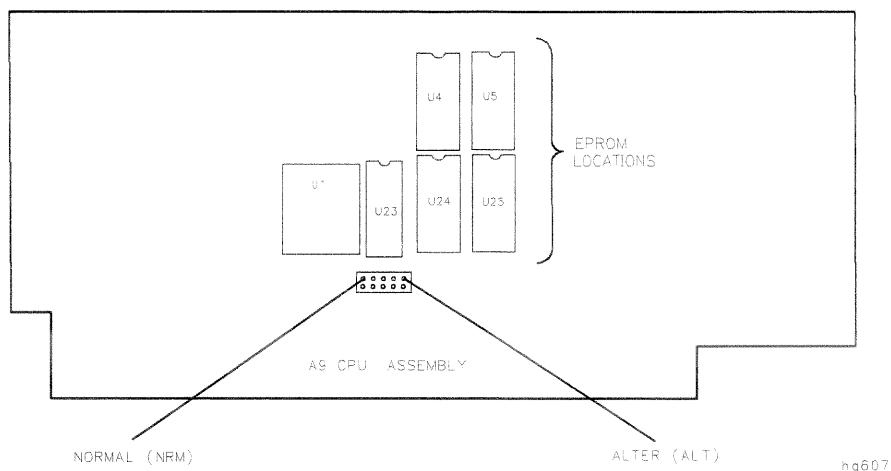


Figure 7-2. Jumper Positions on the A9 CPU

2. Switch on the analyzer and press [PRESET] [SYSTEM] SERVICE MENU TESTS [46] [x1] EXECUTE TEST to generate new analog bus correction constants. Then press [PRESET] [SYSTEM] SERVICE MENU TESTS [45] [x1] EXECUTE TEST to generate default pretune correction constants. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [48] [x1] EXECUTE TEST YES to generate new pretune correction constants.

Note Always press [PRESET] before and after performing an adjustment test.

3. Press [PRESET] and observe the analyzer display:
 - a. No error message: restore the A9 CC jumper to the NRM position. Then refer to "Post-Repair Procedures" in Chapter 14 to verify operation.
 - b. Error message visible: continue with "A4 Sampler/Mixer Check."

A4 Sampler/Mixer Check

The A4, A5, and A6 (R, A and B) sampler/mixers are similar in operation. Any sampler can be used to phase lock the source. To eliminate the possibility of a faulty R sampler, follow this procedure.

1. Remove the W8 cable (A11J1 to A4) from the R-channel sampler (A4) and connect it to either the A-channel sampler (A5) or the B-channel sampler (A6). Refer to Figure 7-3.

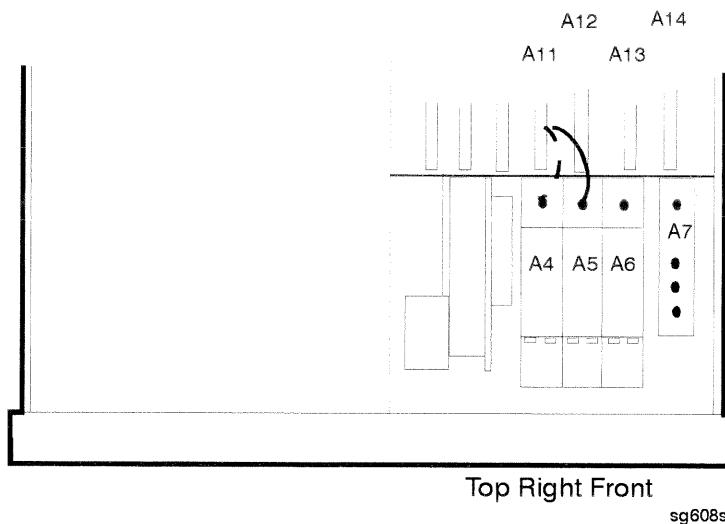


Figure 7-3. Sampler/Mixer to Phase Lock Cable Connection Diagram

2. If you connected W8 to:
 - A5**, press **[MEAS]** Refl FWD: S11 (A/R)
 - A6**, press **[MEAS]** Refl REV: S22 (B/R)
3. Ignore the displayed trace, but check for phase lock error messages. If the phase lock problem persists, the R-channel sampler is *not* the problem.

A3 Source and A11 Phase Lock Check

This procedure checks the source and part of the phase lock assembly. It opens the phase-locked loop and exercises the source by varying the source output frequency with the A11 pretune DAC.

Note If the analyzer failed internal test 48, default pretune correction constants were stored which may result in a constant offset of several MHz. Regardless, continue with this procedure.

Note Use a spectrum analyzer for problems above 100 MHz.

1. Connect the oscilloscope or spectrum analyzer as shown in Figure 7-1. (Set the oscilloscope input impedance to 50 ohms.)
2. Press **[PRESET]** **[SYSTEM]** SERVICE MENU SERVICE MODES SRC ADJUST MENU SRC TUNE ON SRC TUNE FREQ to activate the source tune (SRC TUNE) service mode.
3. Use the front panel knob or front panel keys to set the pretune frequency to 300 kHz, 30 MHz, and 40 MHz. Verify the signal frequency on the oscilloscope.

Note In SRC TUNE mode, the source output frequency changes in 1 to 2 MHz increments and should be 1 to 6 MHz above the indicated output frequency.

4. Check for the frequencies indicated by Table 7-1.

Table 7-1. Output Frequency in SRC Tune Mode

Setting	Observed Frequency
300 kHz	1.3 to 6.3 MHz
30 MHz	31 to 36 MHz
40 MHz	41 to 46 MHz

5. The signal observed on an oscilloscope should be as solid as the signal in Figure 7-4.

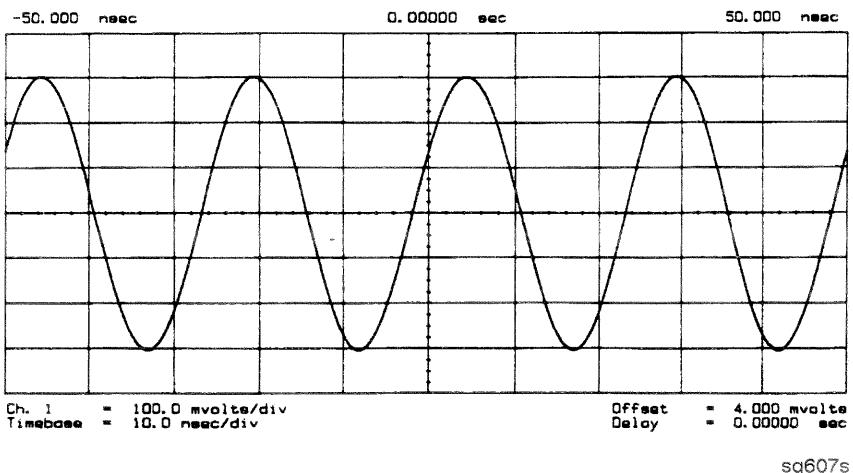
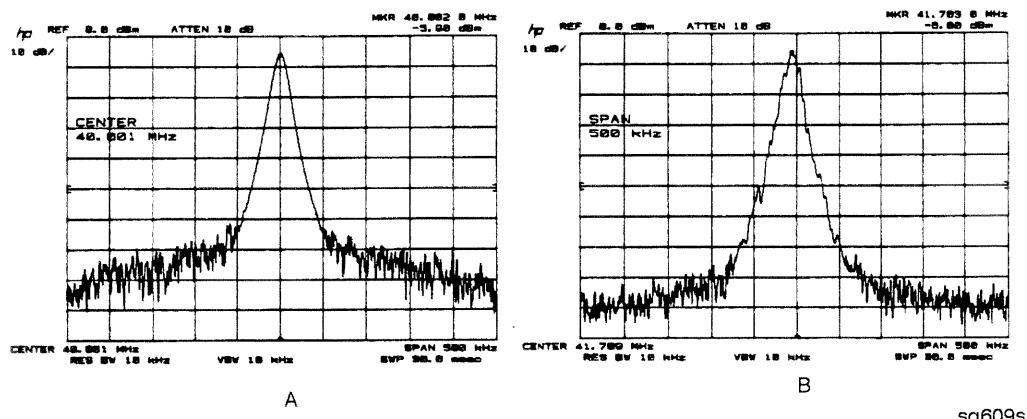


Figure 7-4. Waveform Integrity in SRC Tune Mode

6. The signal observed on the spectrum analyzer will appear jittery as in Figure 7-5 (b), not solid as in Figure 7-5 (a). This is because in SRC TUNE mode the output is not phase locked.



sg609s

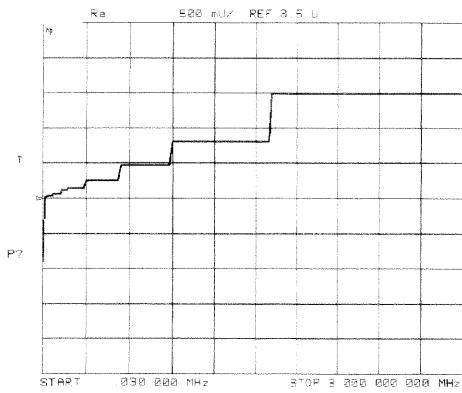
Figure 7-5.
Phase Locked Output Compared to Open Loop Output in SRC Tune Mode

7. Press **[MENU] POWER** to vary the power and check for corresponding level changes on the test instrument. (A power change of 20 dB will change the voltage observed on the oscilloscope by a factor of ten.)
8. Note the results of the frequency and power changes:
 - If the frequency and power output changes are correct, skip ahead to “A12 Reference Check” located in this chapter.
 - If the frequency changes are not correct, continue with “YO Coil Drive Check with Analog Bus.”
 - If the power output changes are not correct, check analog bus node 3.
 - a. Press **SYSTEM SERVICE MENU ANALOG BUS ON [MEAS]**
ANALOG IN Aux Input [FORMAT] MORE REAL [3] [X1].
 - b. Press **[MARKER] 2 [G/n]**. The marker should read approximately 434 mU.
 - c. Press **[MARKER] 4 [G/n]**. The marker should read approximately 646 mU.

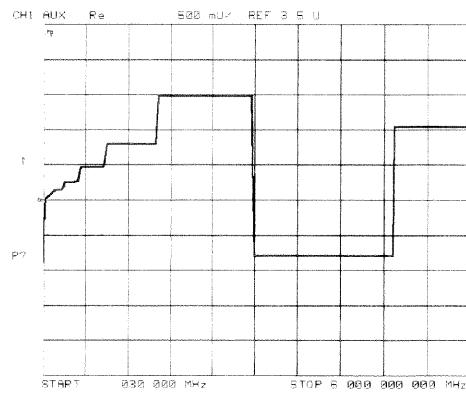
YO Coil Drive Check with Analog Bus

Note If the analog bus is not functional, perform the “YO Drive Coil Check with Oscilloscope” test.

1. Press [PRESET] [SYSTEM] SERVICE MENU ANALOG BUS ON SERVICE MODES
SOURCE PLL OFF [MEAS] ANALOG IN Aux Input COUNTER:ANALOG BUS .
2. Then press [16] [X1] [FORMAT] MORE REAL [SCALE REF] AUTOSCALE . This keystroke sequence lets you check the pretune DAC and the A11 output to the YO coil drive by monitoring the 1 V/GHz signal at analog bus node 16.
3. Compare the waveform to Figure 7-6. If the waveform is incorrect, the A11 phase lock assembly is faulty.



3 GHz 8753D



6 GHz 8753D

sg629s

Figure 7-6. 1V/GHz at Analog Bus Node 16 with Source PLL Off.

7-10 Source Troubleshooting

YO Coil Drive Check with Oscilloscope

Note Use the large extender board for easy access to the voltage points. The extender board is included with the HP 8753 Tool Kit. See Chapter 13, "Replaceable Parts," for part numbers and ordering information.

1. Connect oscilloscope probes to A11P1-1 and A11P1-2. The YO coil drive signal is actually two signals whose voltage difference drives the coil.
2. Press [PRESET] [SYSTEM] SERVICE MENU SERVICE MODES SOURCE PLL OFF to operate the analyzer in a swept open loop mode.
3. Monitor the two YO coil drive lines. In source tune mode the voltage difference should vary from approximately 3.5 to 5.0 volts as shown in Figure 7-7.
 - If the voltages are not correct, replace the faulty A11 assembly.
 - If the output signals from the A11 assembly are correct, replace the faulty A3 source assembly.
 - If neither the A11, nor the A3 assembly is faulty, continue with the next check.

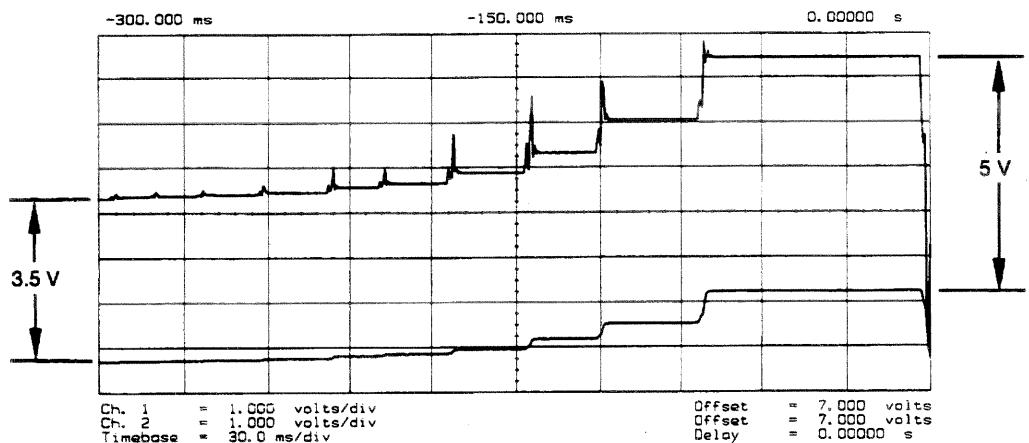


Figure 7-7.
YO- and YO+ Coil Drive Voltage Differences with SOURCE PLL OFF

A12 Reference Check

The signals are evaluated with pass/fail checks. The most efficient way to check the A12 frequency reference signals is to use the analog bus while referring to Table 7-2.

Alternatively, you can use an oscilloscope, while referring to Table 7-3 and Figure 7-8 through Figure 7-14. If any of the observed signals differs from the figures, there is a 90% probability that the A12 assembly is faulty. Either consider the A12 assembly defective or perform the "A12 Digital Control Signals Check."

Both of these procedures are described ahead.

Analog Bus Method

1. Press [PRESET] [SYSTEM] SERVICE MENU ANALOG BUS ON [MEAS]
ANALOG IN Aux Input ANALOG BUS to switch on the analog bus and its counter.
2. Press [21] [x1] to count the frequency of the 100 kHz signal.
3. Press [MENU] CW FREQ [500] [k/m]. Verify that the counter reading (displayed on the analyzer next to cnt:) matches the corresponding 100 kHz value for the CW frequency. (Refer to Table 7-2.)
4. Verify the remaining CW frequencies, comparing the counter reading with the value in Table 7-2:
 - Press [2] [M/ μ].
 - Press [50] [M/ μ].

Table 7-2. Analog Bus Check of Reference Frequencies

CW Frequency	Analog Bus Node 21 100 kHz	Analog Bus Node 24 2nd LO	Analog Bus Node 25 PLREF
500 kHz	0.100 MHz	0.504 MHz	0.500 MHz
2 MHz	0.100 MHz	2.007 MHz	2.000 MHz
50 MHz	0.100 MHz	0.996 MHz	1.000 MHz

NOTE: The counter should indicate the frequencies listed in this table to within $\pm 0.1\%$. Accuracy may vary with gate time and signal strength.

7-12 Source Troubleshooting

5. Press [24] $\times 1$ to count the frequency of the 2nd LO signal.
6. Press [MENU] CW FREQ [500] k/m . Verify that the counter reading matches the corresponding 2nd LO value for the CW frequency. (Refer to Table 7-2.)
7. Verify the remaining CW frequencies, comparing the counter reading with the value in Table 7-2:
 - Press [2] M/μ .
 - Press [50] M/μ .
8. Press [25] $\times 1$ to count the frequency of the PLREF signal.
9. Press [MENU] CW FREQ [500] k/m . Verify that the counter reading matches the corresponding PLREF value for the CW frequency. (Refer to Table 7-2.)
10. Verify the remaining CW frequencies, comparing the counter reading with the value in Table 7-2:
 - Press [2] M/μ .
 - Press [50] M/μ .
11. Check the results.
 - If all the counter readings match the frequencies listed in Table 7-2, skip ahead to “A13/A14 Fractional-NCheck.”
 - If the counter readings are incorrect at the 500 kHz and 2 MHz settings only, go to “FN LO at A12 Check.”
 - If all the counter readings are incorrect at all three CW frequencies, the counter may be faulty. Perform the “Oscilloscope Method” check of the signals described below. (If the signals are good, either the A10 or A14 assemblies could be faulty.)

Oscilloscope Method

You need not use the oscilloscope method unless the analog bus is non-functional or any of the signals fail the specifications listed in Table 7-2.

If the analog bus is non-functional or the previous check has revealed questionable signals, observe the signal(s) with an oscilloscope. Table 7-3 identifies a convenient test point and a plot for the five signals listed.

Table 7-3. A12 Reference Frequencies

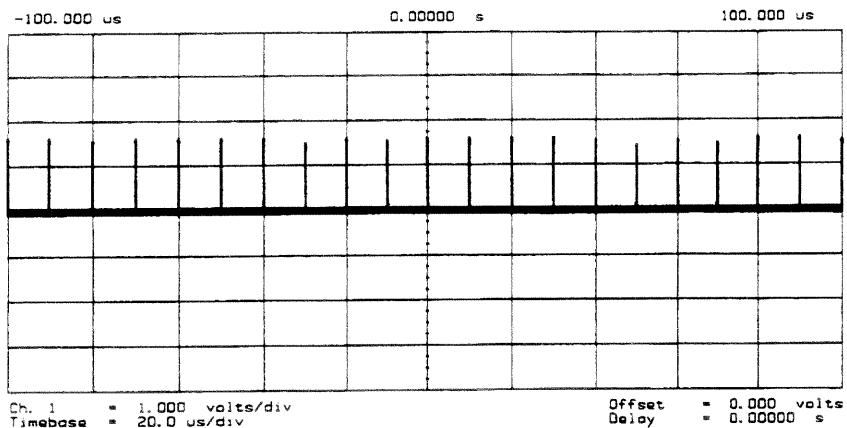
Mnemonic	Signal Description	Location	See Figure	Analyzer Setting
FN100kHzREF	100 kHz Reference	A13TP5	Figure 7-8	any
REF	Phase Lock Reference	A11TP1 Pin 9	Figure 7-9	≥ 16 MHz CW
REF	Phase Lock Reference	A11TP1 Pin 9	Figure 7-10	5 MHz CW
FN LO*	Fractional-N LO	A14J2	Figure 7-11	10 MHz CW
4MHz REF	4 MHz Reference	A12TP9	Figure 7-12	any
2ND LO + / -	Second LO	A12P1-2,4	Figure 7-13	≥ 16 MHz CW
2ND LO + / -	Second LO	A12P1-2,4	Figure 7-14	14 MHz CW

* Not an A12 signal, but required for A12 lowband operation.

7-14 Source Troubleshooting

100 kHz Pulses

The 100 kHz pulses are very narrow and typically 1.5 V in amplitude. You may have to increase the oscilloscope intensity to see these pulses. (See Figure 7-8.)



sg610s

Figure 7-8. Sharp 100 kHz Pulses at A13TP5 (any frequency)

PLREF Waveforms

REF Signal At A11TP1 Pin 9. REF is the buffered PLREF+ signal. The 1st IF is phase locked to this signal. Use an oscilloscope to observe the signal at the frequencies noted in Figure 7-9 and Figure 7-10.

High Band REF Signal. In high band the REF signal is a constant 1 MHz square wave as indicated by Figure 7-9.

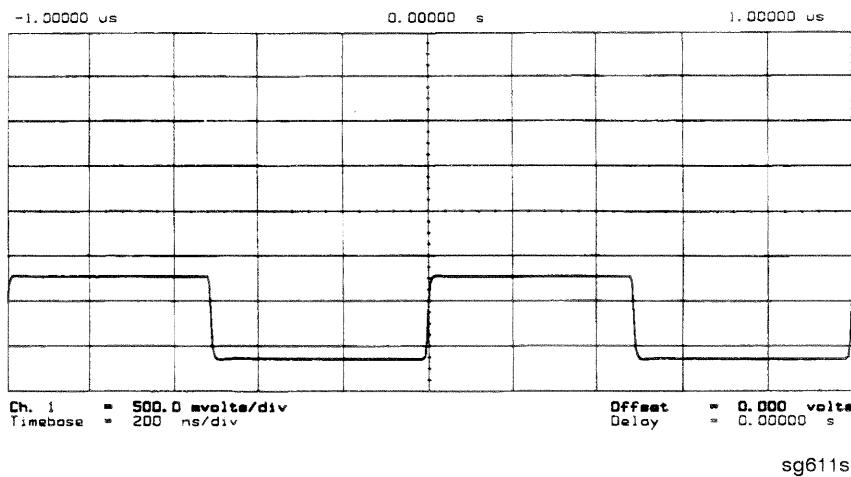


Figure 7-9. High Band REF Signal (≥ 16 MHz CW)

Low Band REF Signal. In low band this signal follows the frequency of the RF output signal. Figure 7-10 illustrates a 5 MHz CW signal.

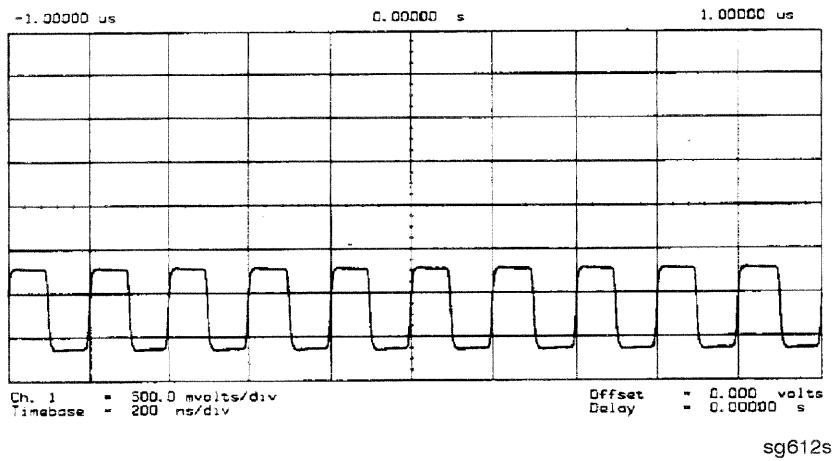


Figure 7-10. REF Signal at A11TP9 (5 MHz CW)

- If REF looks good, skip ahead to “4 MHz Reference Signal.”
- If REF is bad in low band, continue with “FN LO at A12 Check.”

FN LO at A12 Check

1. Use an oscilloscope to observe the FN LO from A14 at the cable end of A14J2. Press [PRESET] [SYSTEM] SERVICE MENU SERVICE MODES FRACN TUNE ON to switch on the fractional-N service mode.
2. Use the front panel knob to vary the frequency from 30 to 60 MHz. The signal should appear similar to Figure 7-11. The display will indicate 10 to 60.8 MHz.
 - If the FN LO signal is good, the A12 assembly is faulty.
 - If the FN LO signal is not good, skip ahead to “A13/A14 Fractional-N Check.”

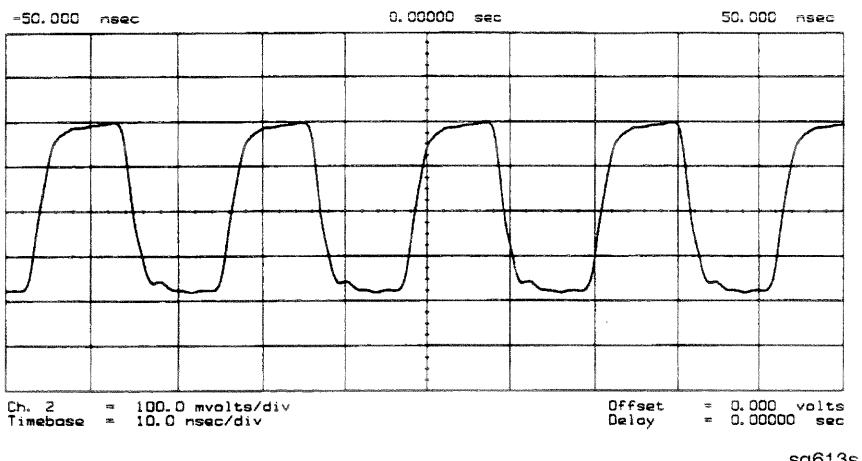


Figure 7-11. Typical FN LO Waveform at A12J1

7-18 Source Troubleshooting

4 MHz Reference Signal

This reference signal is used to control the receiver. If faulty, this signal can cause apparent source problems because the CPU uses receiver data to control the source. At A12TP9 it should appear similar to Figure 7-12.

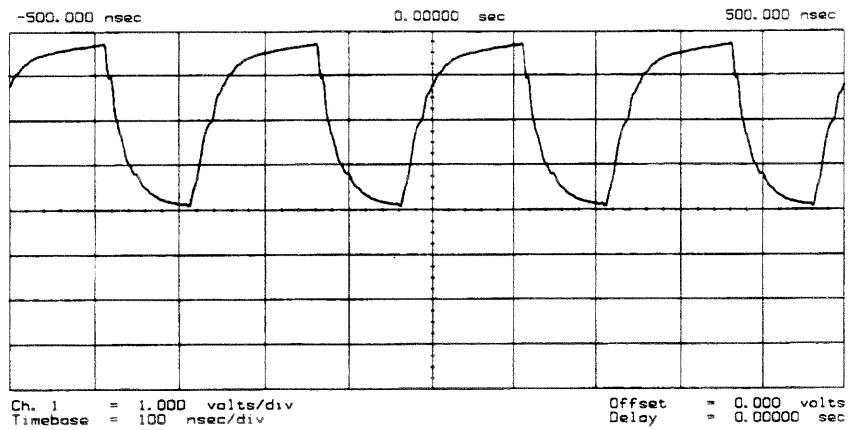


Figure 7-12. 4 MHz Reference Signal at A12TP9 (Preset)

2ND LO Waveforms

The 2nd LO signals appear different in phase and shape at different frequencies. Refer to Table 7-3 for convenient test points.

90 Degree Phase Offset of 2nd LO Signals in High Band. In high band, the 2nd LO is 996 kHz. As indicated by Figure 7-13, the 2nd LO actually consists of two signals 90 degrees out of phase.

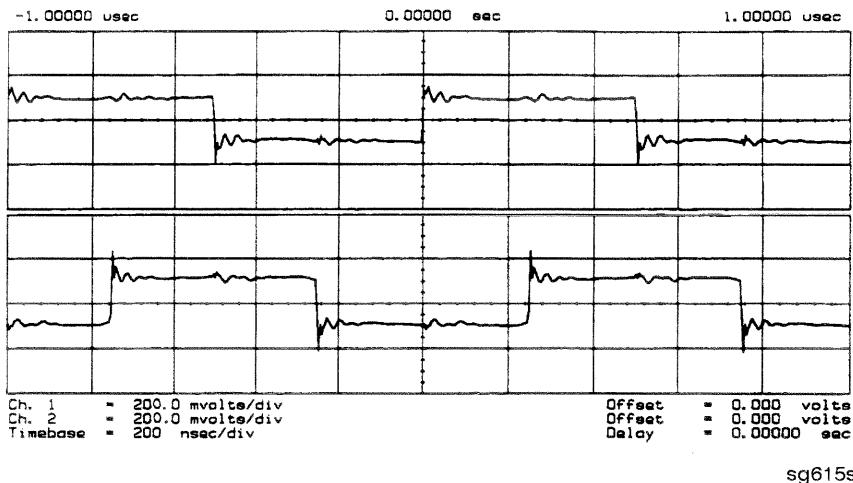


Figure 7-13.

90 Degree Phase Offset of High Band 2nd LO Signals (≥ 16 MHz CW)

In-Phase 2nd LO Signals in Low Band. The 2nd LO signals in low band, as shown in Figure 7-14, are not phase shifted. In low band these signals track the RF output with a 4 kHz offset.

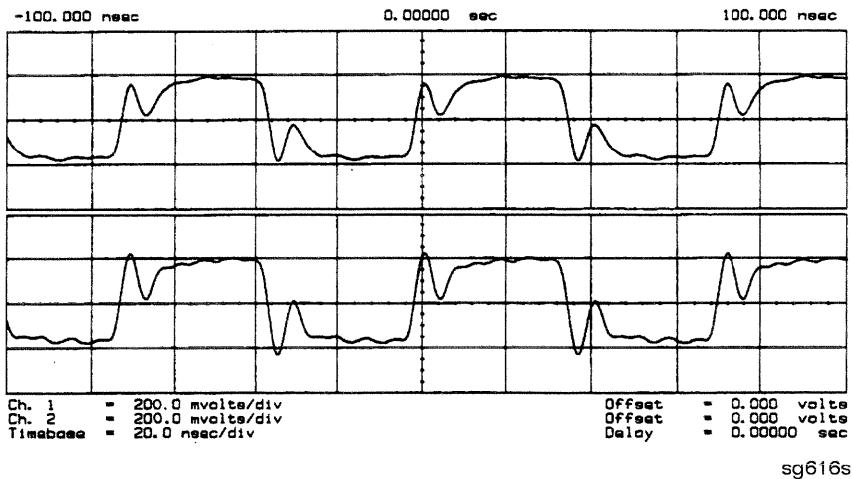


Figure 7-14. In-Phase Low Band 2nd LO Signals (14 MHz CW)

If any of the signals of Table 7-2 are incorrect, the probability is 90% that the A12 assembly is faulty. Either consider the A12 assembly faulty or perform the "A12 Digital Control Signals Check" described ahead.

A12 Digital Control Signals Check

Several digital control signals must be functional for the A12 assembly to operate properly. Check the control lines listed in Table 7-4 with the oscilloscope in the high input impedance setting.

Table 7-4. A12-Related Digital Control Signals

Mnemonic	Signal Description	Location	See Figure	Analyzer Setting
L ENREF	L=Reference Enable	A12P2-16	Figure 7-15	Preset
L HB	L=High Band	A12P2-32	Figure 7-16	Preset
L LB	L=Low Band	A12P1-23	Figure 7-18	Preset

L ENREF Line. This is a TTL signal. To observe it, trigger on the negative edge. In preset state, the signal should show activity similar to Figure 7-15.

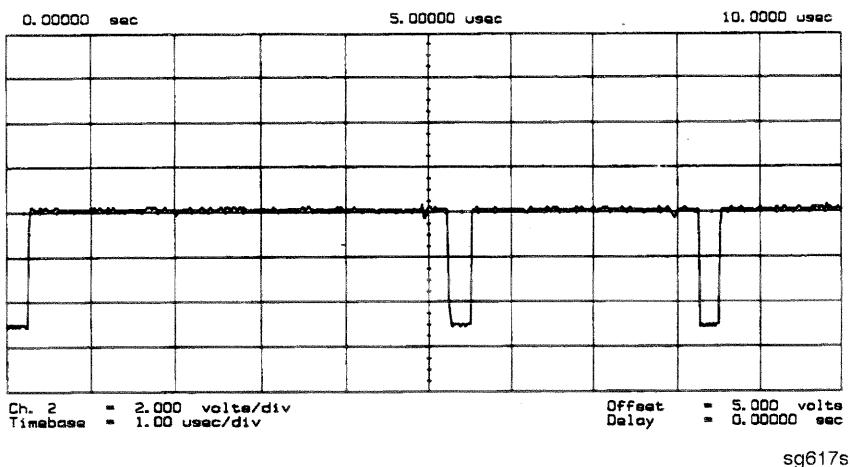
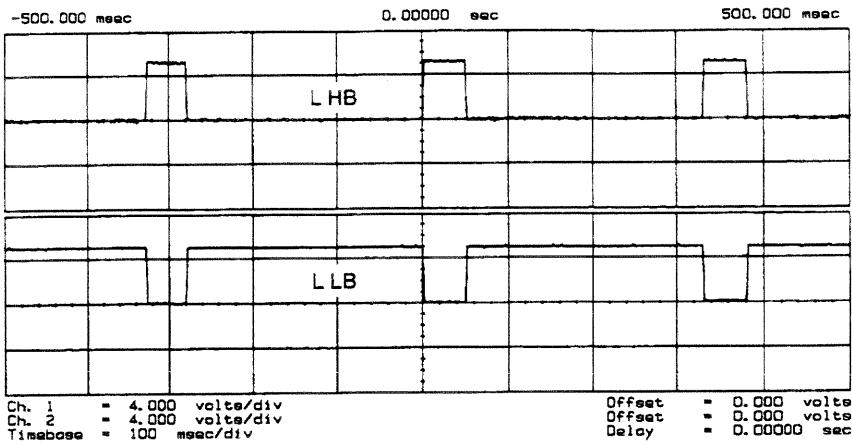


Figure 7-15. L ENREF Line at A12P2-16 (Preset)

L HB and L LB Lines. These complementary signals toggle when the instrument switches from low band to high band as illustrated by Figure 7-16.



sg618s

Figure 7-16. Complementary L HB and L LB Signals (Preset)

If all of the digital signals appeared good, the A12 assembly is faulty.

A13/A14 Fractional-N Check

Use the analog bus or an oscilloscope to check the A14 VCO's ability to sweep from 30 MHz to 60 MHz. The faster analog bus method should suffice unless problems are detected.

Fractional-N Check with Analog Bus

1. Press [PRESET] [SYSTEM] SERVICE MENU ANALOG BUS ON [MEAS]
ANALOG IN Aux Input FRAC N to switch on the analog bus and the fractional-N counter.
2. Then press [MENU] [CW FREQ] to set the analyzer to CW mode.
3. Set the instrument as indicated in Table 7-5 and see whether the VCO generates the frequencies listed.

Table 7-5. VCO Range Check Frequencies

Instrument Setting	Counter Reading
31 MHz	30±0.030 MHz
60.999999 MHz	60±0.060 MHz

4. Check the counter reading at the frequencies indicated.

- If the readings are within the limits specified, the probability is greater than 90% that the fractional-N assemblies are functional. Either skip ahead to the “A7 Pulse Generator Check” or perform the more conclusive “A14 VCO Range Check with Oscilloscope” described below.
- If the readings fail the specified limits, perform the “A14 VCO Excercise.”

A14 VCO Range Check with Oscilloscope

1. Remove the W9 HI OUT cable (A14J1 to A7) from the A7 assembly and connect it to an oscilloscope set for 50 ohm input impedance. Switch on the analyzer.
2. Press [PRESET] [SYSTEM] SERVICE MENU SERVICE MODES FRACN TUNE ON to activate the FRACN TUNE service mode. See Chapter 10, “Service Key Menus and Error Messages,” for more information on the FRACN TUNE mode.
3. Vary the fractional-N VCO frequency with the front panel knob and check the signal with the oscilloscope. The waveform should resemble Figure 7-17, Figure 7-18, and Figure 7-19.

If the fractional-N output signals are correct, continue source troubleshooting by skipping ahead to “A7 Pulse Generator Check.”

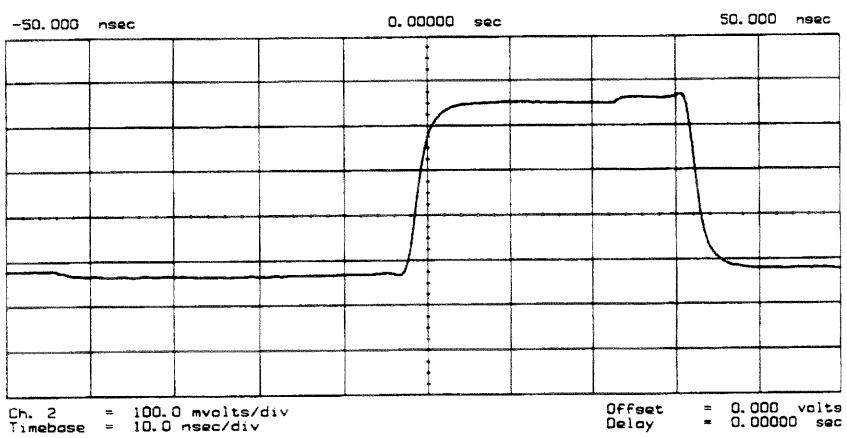


Figure 7-17. 10 MHz HI OUT Waveform from A14J1

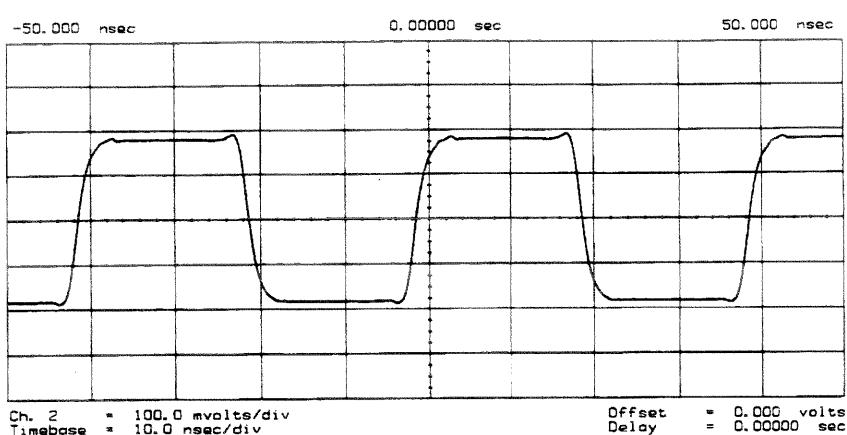


Figure 7-18. 25 MHz HI OUT Waveform from A14J1

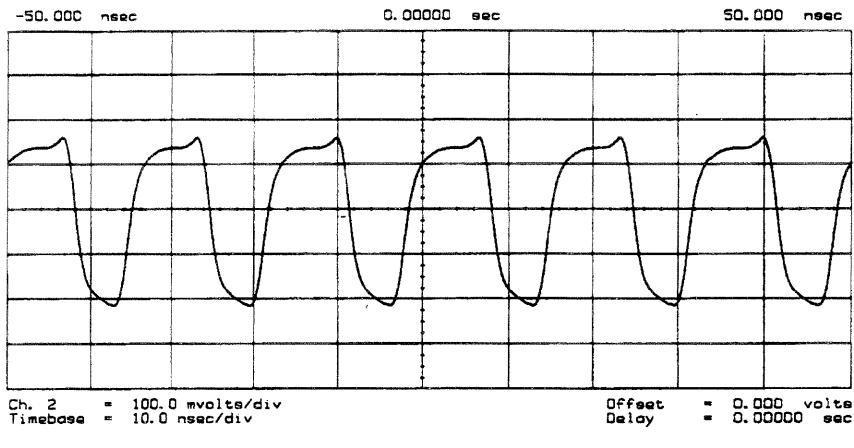


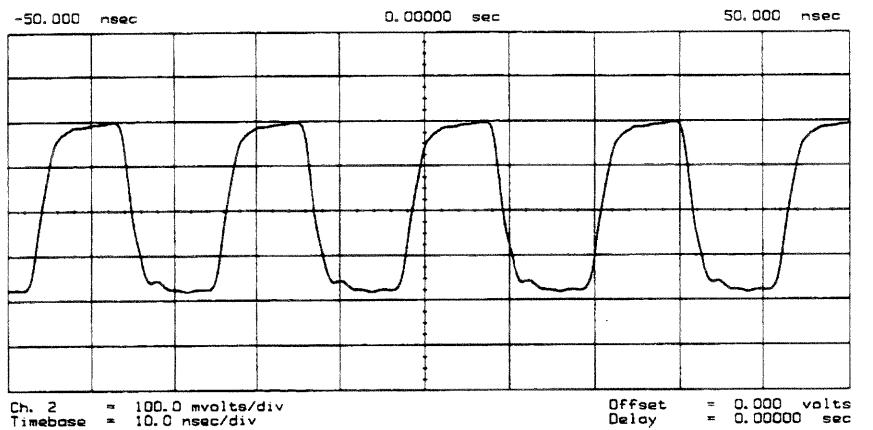
Figure 7-19. 60 MHz HI OUT Waveform from A14J1

A14 VCO Exercise

The nominal tuning voltage range of the VCO is +10 to -5 volts. When the analyzer is in operation, this voltage is supplied by the A13 assembly. This procedure substitutes a power supply for the A13 assembly to check the frequency range of the A14 VCO.

1. Switch off the analyzer and remove the A13 assembly.
2. Put the A14 assembly on an extender board and switch on the instrument.
3. Prepare to monitor the VCO frequency, either by:
 - a. Activating the analog bus and setting the internal counter to the FRACN node, or
 - b. Connecting an oscilloscope to A14J2 (labeled LO OUT) and looking for waveforms similar to Figure 7-20.

7-26 Source Troubleshooting



sg613s

Figure 7-20. LO OUT Waveform at A14J2

4. Vary the voltage at A14TP14 from +10 to -5 volts either by:
 - a. Connecting an appropriate external power supply to A14TP14, or
 - b. First jumping the +15 V internal power supply from A8TP8 to A14TP14 and then jumping the -5.2 V supply from A8TP10 to A14TP14.
5. Confirm that the VCO frequency changes from approximately 30 MHz or less to 60 MHz or more.
6. If this procedure produces unexpected results, the A14 assembly is faulty.
7. If this procedure produces the expected results, continue with the "A14 Divide-by N Circuit Check."

A14 Divide-by-N Circuit Check

Note	The A13 assembly should still be out of the instrument and the A14 assembly on an extender board.
-------------	---

1. Ground A14TP14 and confirm (as in the A14 VCO Exercise) that the VCO oscillates at approximately 50 to 55 MHz.
2. Put the analyzer in CW mode (to avoid relock transitions) and activate the FRACN TUNE service mode.
3. Connect an oscilloscope to A14J3 and observe the output.
4. With the FRACN TUNE service feature, vary the frequency from 30 MHz to 60.8 MHz.
5. The period of the observed signal should vary from $5.5 \mu\text{s}$ to $11 \mu\text{s}$.
 - If this procedure produces unexpected results, the A14 assembly is faulty.
 - If this procedure produces the expected results, perform the “A14-to-A13 Digital Control Signals Check.”
6. Remember to replace the A13 assembly.

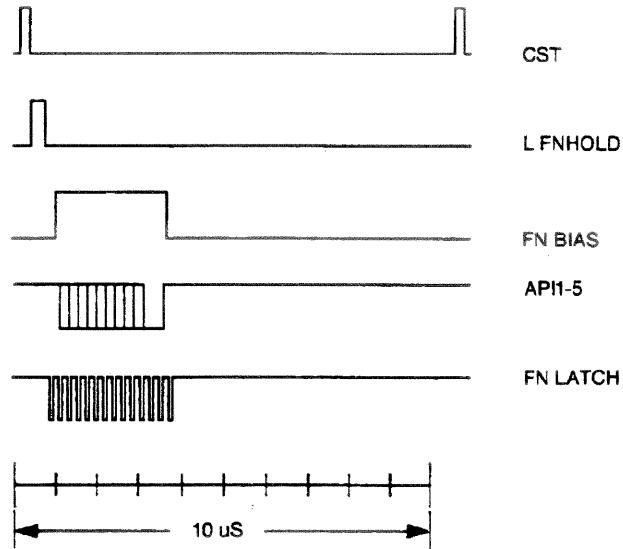
A14-to-A13 Digital Control Signals Check.

The A14 assembly generates a TTL cycle start (CST) signal every 10 microseconds. If the VCO is oscillating and the CST signal is not detectable at A14TP3, the A14 assembly is non-functional.

Use the CST signal as an external trigger for the oscilloscope and monitor the signals in Table 7-6. Since these TTL signals are generated by A14 to control A13, check them at A13 first. Place A13 on the large extender board. The signals should look similar to Figure 7-21. If these signals are good, the A13 assembly is defective.

Table 7-6. A14-to-A13 Digital Control Signal Locations

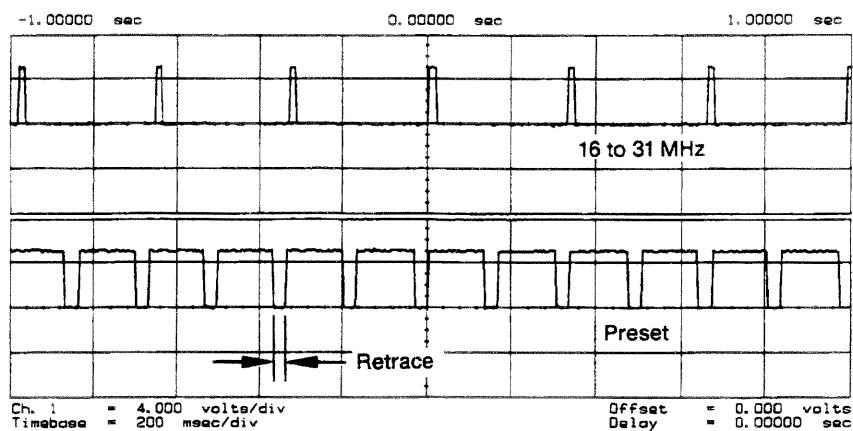
Mnemonic	A13 Location	A14 Location
CST	none	TP3
L FNHOLD	P2-2	P2-2
FNBIA5	P2-5	P2-5
API1	P2-32	P2-32
API2	P2-3	P2-3
API3	P2-34	P2-34
API4	P2-4	P2-4
API5	P2-35	P2-35
NLATCH	P1-28	P1-58



sg622s

Figure 7-21. A14 Generated Digital Control Signals

H MB Line. This signal is active during the 16 MHz to 31 MHz sweep. The upper trace of Figure 7-22 shows relative inactivity of this signal during preset condition. The lower trace shows its status during a 16 MHz to 31 MHz sweep with inactivity during retrace only.



sg623s

Figure 7-22.
H MB Signal at A14P1-5 (Preset and 16 MHz to 31 MHz Sweep)

7-30 Source Troubleshooting

A7 Pulse Generator Check

The pulse generator affects phase lock in high band only. It can be checked with either a spectrum analyzer or an oscilloscope.

A7 Pulse Generator Check with Spectrum Analyzer

1. Remove the A7-to-A6 SMB cable (W7) from the A7 pulse generator assembly. Set the analyzer to generate a 16 MHz CW signal. Connect the spectrum analyzer to the A7 output connector and observe the signal. The A7 comb should resemble the spectral display in Figure 7-23.

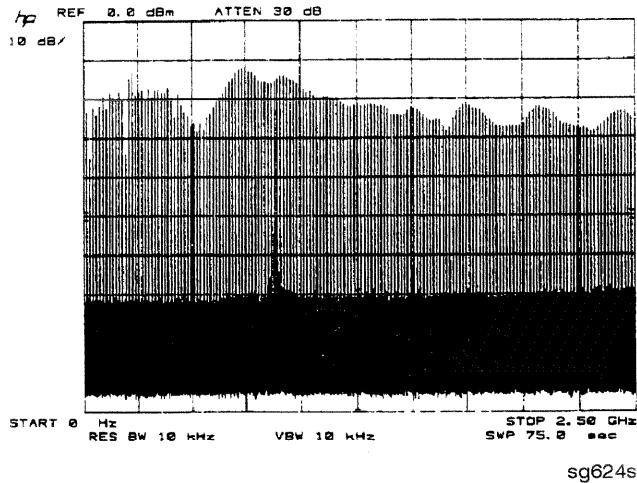


Figure 7-23. Pulse Generator Output

2. If the analyzer malfunction relates to a particular frequency or range, look more closely at the comb tooth there. Adjust the spectrum analyzer span and bandwidth as required. Even at 3 GHz, the comb should look as clean as Figure 7-24. For Option 006 instruments at 6 GHz the comb tooth level should be approximately -46 dBm.

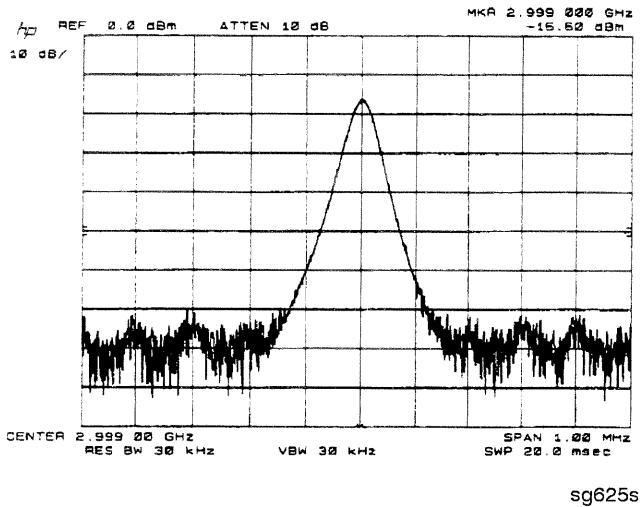


Figure 7-24. High Quality Comb Tooth at 3 GHz

3. If the signal at the A7 output is good, check the A7-to-A4 cable.
4. If the signal is not as clean as Figure 7-24, observe the HI OUT input signal to the A7 assembly.
 - a. On the network analyzer, press **SYSTEM** **SERVICE MENU** **SERVICE MODES** **PLL AUTO OFF**. Otherwise do not readjust the instrument. Remove the A14-to-A7 SMB cable (W9) from the A7 pulse generator assembly. ($CW \approx 16 \text{ MHz}$)
 - b. Set the spectrum analyzer to a center frequency of 45 MHz and a span of 30 MHz. Connect it to the A14-to-A7 cable still attached to the A14 assembly. Narrow the span and bandwidth to observe the signal closely.
5. If the HI OUT signal is as clean as Figure 7-25, the A7 assembly is faulty. Otherwise, check the A14-to-A7 cable or recheck the A13/A14 fractional-N as described ahead.

Rechecking the A13/A14 Fractional-N

Some phase lock problems may result from phase noise problems in the fractional-N loop. To troubleshoot this unusual failure mode, do the following:

1. Set the network analyzer at 60 MHz in the FRACN TUNE mode.

7-32 Source Troubleshooting

2. Use a spectrum analyzer, to examine the HI OUT signal from the A14 assembly. The signal should appear as clean as Figure 7-25. The comb shape may vary from pulse generator to pulse generator.

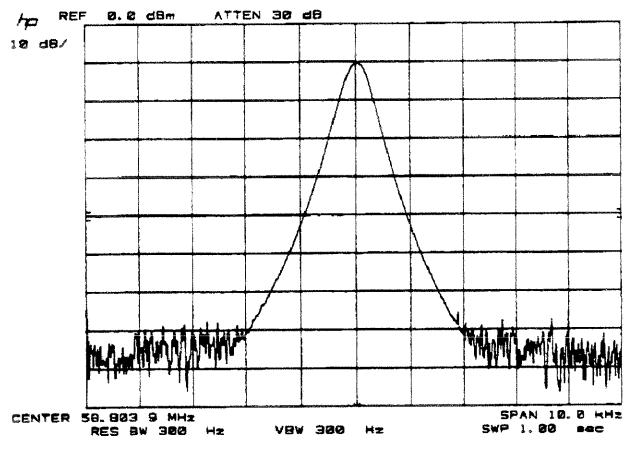


Figure 7-25. Stable HI OUT Signal in FRACN TUNE Mode

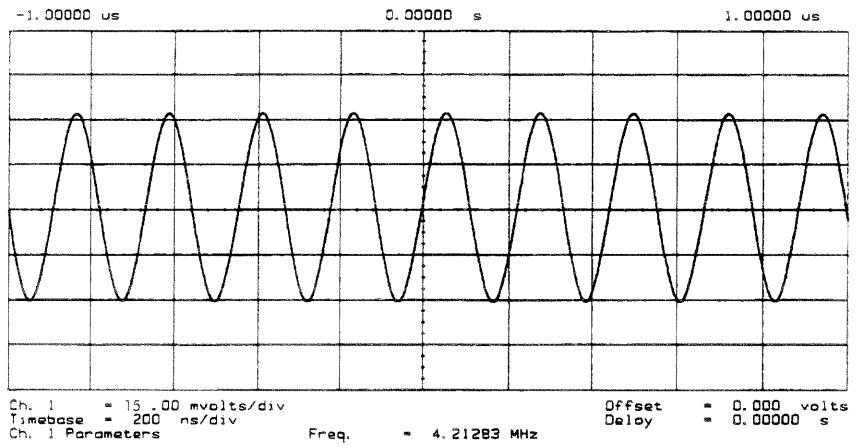
A7 Pulse Generator Check with Oscilloscope

Perform this check if a spectrum analyzer is not available.

1. Remove the A4-to-A11 SMB cable from the A4 (R) sampler/mixer output. Connect the oscilloscope to the A4 output (1st IF).
2. Activate the FRACN TUNE service mode and tune the fractional-N to 50 MHz. Press **SYSTEM SERVICE MENU SERVICE MODES FRACN TUNE ON** **50 [M/ μ]**.
3. Activate the SRC TUNE service mode of the analyzer and tune the source to 50 MHz. Press **SRC TUNE ON SRC TUNE FREQ** **50 [M/ μ]**.
4. Set the SRC TUNE frequency to those listed in Table 7-7 and observe the 1st IF waveforms. They should appear similar to Figure 7-26.
 - If the signals observed are proper, continue "A11 Phase Lock Check."
 - If the signals observed are questionable, use a spectrum analyzer to perform the preceding "A7 Pulse Generator Check with Spectrum Analyzer."

Table 7-7. 1st IF Waveform Settings

SRC TUNE	FRACN	Harmonic	1st IF
50 MHz	50 MHz	1	1 to 6 MHz
250 MHz	50 MHz	5	1 to 6 MHz
2550 MHz	50 MHz	51	1 to 6 MHz



sg627s

Figure 7-26. Typical 1st IF Waveform in FRACN TUNE/SRC TUNE Mode

A11 Phase Lock Check

At this point, the A11 phase lock assembly appears to be faulty (its inputs should have been verified already). Nevertheless, you may elect to use the phase lock diagnostic routines or check the relevant signals at the assembly itself for confirmation.

Note	If external source mode is the only operating mode with phase lock problems, replace the A11 phase lock assembly.
-------------	---

7-34 Source Troubleshooting

Phase Lock Check with PLL DIAG

Refer to "Phase Lock Diagnostic Tools" in "Source Group Troubleshooting Appendix" at the end of this chapter for an explanation of the error messages and the diagnostic routines. Follow the steps there to determine in which state the phase lock is lost.

- If NO IF FOUND is displayed, confirm that the analog bus is functional and perform the "Source Pretune Correction Constants (Test 48)" as outlined in Chapter 3, "Adjustments and Correction Constants."
- If phase lock is lost in the ACQUIRE state, the A11 assembly is faulty.
- If phase lock is lost in the TRACK state, troubleshoot source phase lock loop components other than the A11 assembly.

Phase Lock Check by Signal Examination

To confirm that the A11 assembly is receiving the signals required for its proper operation, perform the following steps.

1. Place the A11 assembly on the large extender board.
2. Switch on the analyzer and press [PRESET].
3. Check for the signals listed in Table 7-8.

Table 7-8. A11 Input Signals

Mnemonic	I/O	Access	See Figure	Notes
FM COIL -	O	A11P1-3,33	Figure 7-27	Aids YO COIL in setting YIG. Press [PRESET] [MENU] NUMBER OF POINTS [3] [x1] to observe this signal.
REF	I	A11TP9	Figure 7-9, Figure 7-10	Observe both low band and high band CW frequencies.
YO COIL +	O	A11P1-2,32	Figure 7-7	Use SOURCE PLL OFF.
YO COIL -	O	A11P1-1,31	Figure 7-7	
1ST IF	I	A11 PL IF IN	Figure 7-26	Check for 1 MHz with tee a A11 jack (not at cable end) in high band.

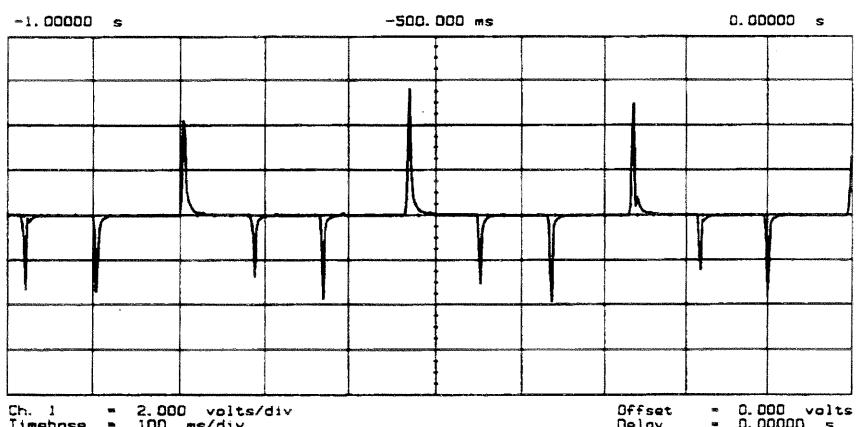


Figure 7-27. FM Coil – Plot with 3 Point Sweep

4. If any of the input signal is not proper, refer to the overall block diagram in Chapter 4, "Start Troubleshooting Here," as an aid to trouble shooting the problem to its source.
5. If any of the output signals is not proper, the A11 assembly is faulty.

7-36 Source Troubleshooting

Source Group Troubleshooting Appendix

Troubleshooting Source Problems with the Analog Bus

The analog bus can perform a variety of fast checks. However, it too is subject to failure and thus should be tested prior to use. You should have done this in Chapter 4, “Start Troubleshooting Here.”

To use the analog bus to check any one of the nodes, press [PRESET] [SYSTEM] SERVICE MENU ANALOG BUS IN. Then press [MEAS] ANALOG IN Aux Input and enter the analog bus node number followed by [x1]. Refer to “Analog Bus” in Chapter 10, “Service Key Menus and Error Messages,” for additional information.

Phase Lock Diagnostic Tools

- error messages
- diagnostic routines

Phase Lock Error Messages

All phase lock error messages can result from improper front panel connections.

NO IF FOUND: CHECK R INPUT LEVEL means no IF was detected during pretune: a source problem. Perform the “A4 Sampler/Mixer Check.”

NO PHASE LOCK: CHECK R INPUT LEVEL means the IF was not acquired after pretune: a source problem. Perform the “A4 Sampler/Mixer Check.” earlier in this chapter.

PHASE LOCK CAL FAILED means that a calculation of pretune values was not successful: a source or receiver failure. Perform the “Source Pretune Correction Constants” routine as outlined in Chapter 3, “Adjustments and Correction Constants.” If the analyzer fails that routine, perform the “A4 Sampler/Mixer Check.”

PHASE LOCK LOST means that phase lock was lost or interrupted before the band sweep ended: a source problem. Refer to “Phase Lock Diagnostic Routines” next to access the phase lock loop diagnostic service routine. Then troubleshoot the problem by following the procedures in this chapter.

Phase Lock Diagnostic Routines

Perform the following steps to determine at what frequencies and bands the phase lock problem occurs.

1. Press **[PRESET] [SYSTEM] SERVICE MENU SERVICE MODES PLL AUTO OFF** to switch off the automatic phase-locked loop. Normally, when the phase-locked loop detects lock problems, it automatically aborts the sweep and attempts to recalibrate the pretune cycle. Switching off PLL AUTO defeats this routine.
2. Press **PLL DIAG ON** to switch on the phase-locked loop diagnostic service mode. In this mode, the phase lock cycle and subsweep number are displayed on the analyzer display. (See "Service Modes Menu" in Chapter 10, "Service Key Menus and Error Messages," for more information.)
3. Press **PLL PAUSE** to pause the phase lock sequence and determine where the source is trying to tune when lock is lost.

Refer to "Source Theory Overview" in Chapter 12, "Theory of Operation," for additional information regarding band related problems. Then use the procedures in this chapter to check source functions at specific frequencies.

Broadband Power Problems

This section assumes that a power problem exists across the full frequency range, but that no error message is displayed on the analyzer. The problem may effect port 1, port 2, or both. Assemblies in question include:

A3 source

A21, A22 directional couplers

A24 solid-state transfer switch

any cables from the A3 source to the outputs of port 1 or port 2

8

Receiver Troubleshooting

Use this procedure only if you have read Chapter 4, “Start Troubleshooting Here.” Follow the procedures in the order given, unless instructed otherwise.

The receiver group assemblies consist of the following:

- A4/5/6 sampler/mixer assemblies
- A10 digital IF assembly

Assembly Replacement Sequence

The following steps show the sequence to replace an assembly in an HP 8753D network analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Receiver Failure Error Messages

The error messages which indicate receiver group problems may be caused by the instrument itself or by external devices or connections. The following three error messages share the same description.

- CAUTION: OVERLOAD ON INPUT A, POWER REDUCED
- CAUTION: OVERLOAD ON INPUT B, POWER REDUCED
- CAUTION: OVERLOAD ON INPUT R, POWER REDUCED

If any of the above error messages appear, the analyzer has exceeded approximately +14 dBm at one of the test ports. The RF output power is automatically reduced to -85 dBm. The annotation P↓ appears in the left margin of the display to indicate that the power trip function has been activated. To reset the analyzer's power and regain control of the power level, do the following:

1. Remove any devices under test which may have contributed excess power to the input.
2. Press **[MENU] POWER [0] [X1] SOURCE POWER ON** to return the power level to the preset state.
 - If the power trip indicator (P↓) does not reappear, reconfigure the test setup to keep input power levels at 0 dBm or below.
 - If P↓ reappears, continue with "Check the A and B Inputs."

Check the A and B Inputs

Good inputs produce traces similar to Figure 8-2 in terms of flatness. To examine both input traces, do the following:

1. Connect the equipment as shown in Figure 8-1. (The thru cable is HP part number 8120-4779.)

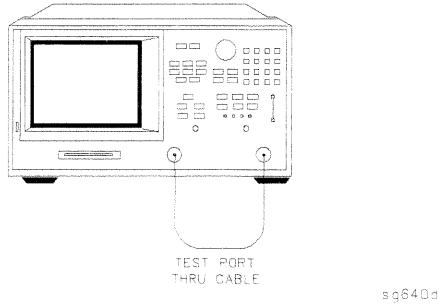


Figure 8-1. Equipment Setup

2. Check the flatness of the input A trace by comparing it with the trace in Figure 8-2.

Press [PRESET] [MEAS] INPUT PORTS A TEST PORT 2 [SCALE REF]
[AUTO SCALE].

3. Check the flatness of the input B trace by comparing it with the trace in Figure 8-2.

Press [MEAS] INPUT PORTS TEST PORT 1 B.

- If neither of the input traces resemble Figure 8-2, continue with "Troubleshooting When All Inputs Look Bad."
- If at least one input trace resembles Figure 8-2, continue with "Troubleshooting When One or More Inputs Look Good."

8-4 Receiver Troubleshooting

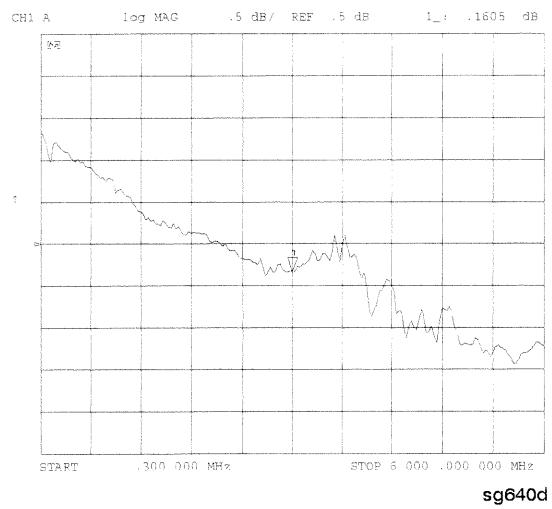


Figure 8-2. Typical Good Trace

Troubleshooting When All Inputs Look Bad

Run Internal Tests 18 and 17

1. Press [PRESET] [SYSTEM] SERVICE MENU TESTS [18] [x1] EXECUTE TEST to run the ADC offset.
2. Then, when the analyzer finishes test 18, press [17] [x1] EXECUTE TEST to run the ADC linearity test.

If either of these tests FAIL, the A10 assembly is probably faulty. This can be confirmed by checking the 4 MHz signal and substituting the A10 assembly or checking the signals listed in Table 8-1.

Check 2nd LO

Check the 2nd LO signal. Refer to the “A12 Reference Check” section of Chapter 7, “Source Troubleshooting” for analog bus and oscilloscope checks of the 2nd LO and waveform illustrations.

- If the analyzer passes the checks, continue to “Check the 4 MHz REF Signal.”
- If the analyzer fails the checks, perform the high/low band transition adjustment. If the adjustment fails, or brings no improvement, replace A12.

Check the 4 MHz REF Signal

1. Press [PRESET].
2. Use an oscilloscope to observe the 4 MHz reference signal at A10P2-6.
 - If the signal does not resemble Figure 8-3, troubleshoot the signal source (A12P2-36) and path.
 - If the signal is good, the probability is greater than 90% that the A10 assembly is faulty. For confirmation, perform "Check A10 by Substitution or Signal Examination."

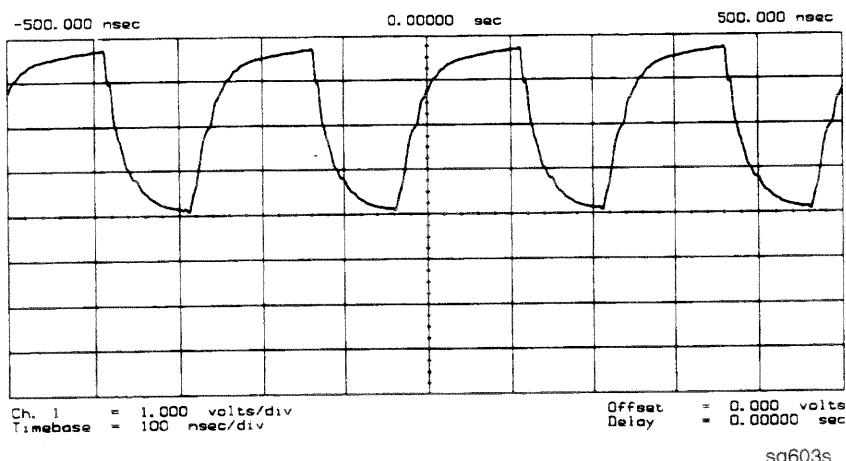


Figure 8-3. 4 MHz REF Waveform

Check A10 by Substitution or Signal Examination

If the 4 MHz REF signal is good at the A10 digital IF assembly, check the A10 assembly by one of the following methods:

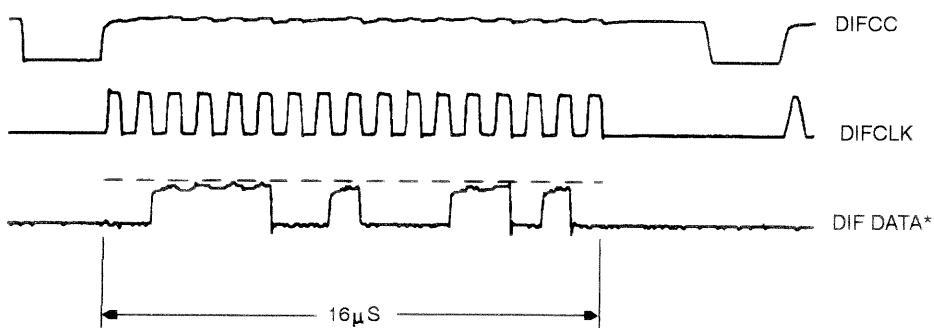
- Substitute another A10 assembly or
- Check the signal/control lines required for its operation. The pins and signal sources of those lines are identified in Table 8-1. It is possible that the A9 assembly may not be providing the necessary signals. These signal checks allow you to determine which assembly is faulty. Some of the waveforms are illustrated by Figure 8-4 and Figure 8-5.

If the substitute assembly shows no improvement or if all of the input signals are valid, continue with “Check the 4 kHz Signal.” Otherwise troubleshoot the suspect signal(s) or consider the A10 assembly faulty.

Table 8-1. Signals Required for A10 Assembly Operation

Mnemonic	Description	A10 Location	Signal Source	See Figure
DIFD0	Digital IF data 0 (LSB)	P2-27	A9P2-27	*
DIFD1	Digital IF data 1	P2-57	A9P2-57	*
DIFD2	Digital IF data 2	P2-28	A9P2-28	*
DIFD3	Digital IF data 3	P2-58	A9P2-58	*
DIFD4	Digital IF data 4	P2-29	A9P2-29	*
DIFD5	Digital IF data 5	P2-59	A9P2-59	*
DIFD6	Digital IF data 6	P2-30	A9P2-30	*
DIFD7	Digital IF data 7 (MSB)	P2-60	A9P2-60	*
L DIFEN0	Digital IF enable 0	P2-34	A9P2-34	*
L DIFEN1	Digital IF enable 1	P2-5	A9P2-5	*
L DIFEN2	Digital IF enable 2	P2-35	A9P2-35	*
DIFCC	Digital IF conversion comp.	P2-33	A10P2-33	Figure 8-4
DIFCLK	Digital IF serial clock	P2-4	A10P2-4	Figure 8-4
DIF DATA	Digital IF serial data out	P2-3	A10P2-3	Figure 8-4
L ENDIF	L=enable digital IF	P2-17	A9P2-17	Figure 8-5
L INTCP0	L=interrupt, DSP	P2-2	A10P2-2	Figure 8-5

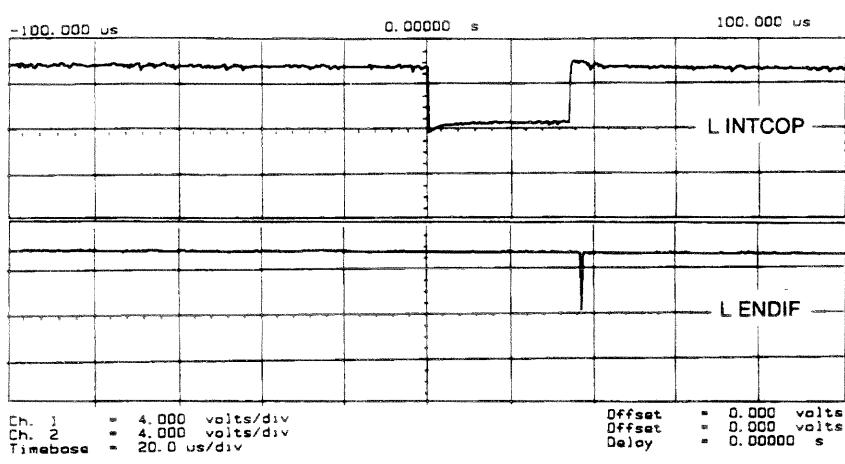
*Check for TTL activity.



* DIF DATA consists of 16 serial bits per input conversion.
the LSB is on the right side and is the most volatile.

sg602s

Figure 8-4. Digital Data Lines Observed Using L INTCOP as Trigger



sg604s

Figure 8-5. Digital Control Lines Observed Using L INTCOP as Trigger

8-10 Receiver Troubleshooting

Troubleshooting When One or More Inputs Look Good

Since at least one input is good, all of the common receiver circuitry beyond the multiplexer is functional. Only the status of the individual sampler/mixers and their individual signal paths is undetermined.

Check the 4 kHz Signal

1. Press **PRESET** **MENU** **CW FREQ**.
2. Use an oscilloscope to check the 4 kHz output of the sampler/mixer in question at the A10 assembly. The input and output access pins are listed in Table 8-2. The signal should resemble the waveform of Figure 8-6.
 - If the signal is good, continue with “Check the Trace with the Sampler Correction Constants Off.”
 - If the signal is bad, skip ahead to “Check 1st LO Signal at Sampler/Mixer.”

Table 8-2. 2nd IF (4 kHz) Signal Locations

Mnemonic	Description	A10 Location	Signal Source
IFR	4 kHz	A10P1-1, 31	A4P1-6
IFA	4 kHz	A10P1-4, 34	A5P1-6
IFB	4 kHz	A10P1-7, 37	A6P1-6

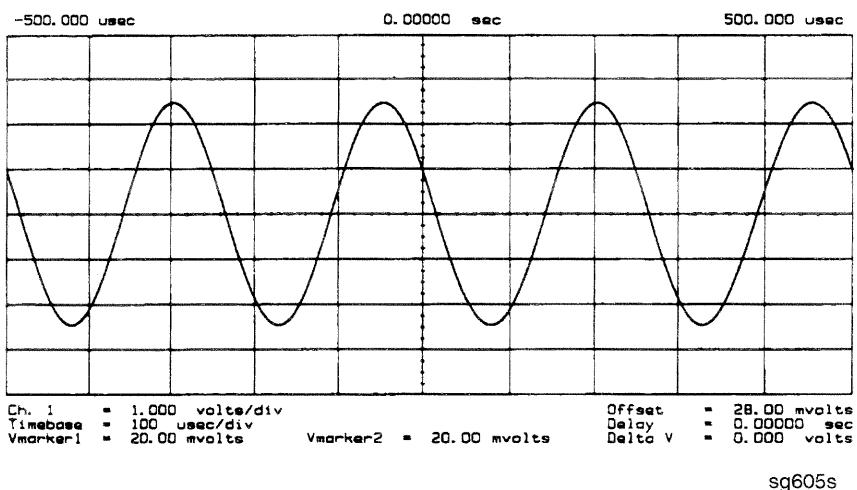


Figure 8-6. 2nd IF (4 kHz) Waveform

Check the Trace with the Sampler Correction Constants Off

1. Press [PRESET] [MEAS] INPUT PORTS A [SCALE REF] AUTO SCALE.
2. The trace is currently being displayed with the sampler correction constants on and should resemble Figure 8-7a.
3. Press [SYSTEM] SERVICE MENU SERVICE MODES MORE SAMPLER COR OFF.
4. The trace is now being displayed with sampler correction constants off and should have worsened to resemble Figure 8-7b.
5. Press SAMPLER COR ON. The trace should improve and resemble Figure 8-7a again.

Note	When the correction constants are switched off, an absolute offset and bandswitch points may be evident.
-------------	--

8-12 Receiver Troubleshooting

If the trace shows no improvement when the sampler correction constants are toggled from off to on, perform the “Sampler Magnitude and Phase Correction Constants (Test 53)” adjustment described in Chapter 3, “Adjustments and Correction Constants.” If the trace remains bad after this adjustment, the A10 assembly is defective.

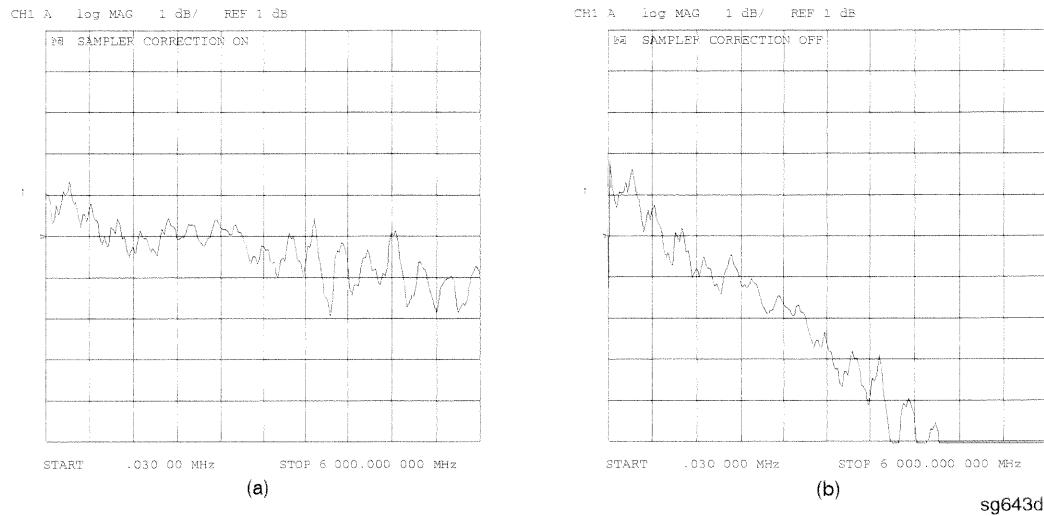


Figure 8-7. Typical Trace with Sampler Correction On and Off

Check 1st LO Signal at Sampler/Mixer

If the 4 kHz signal is bad at the sampler/mixer assembly, check the 1st LO signal where it enters the sampler/mixer assembly in question.

- If the 1st LO is faulty, check the 1st LO signal at its output connector on the A7 assembly to determine if the failure is in the cable or the assembly.
- If the 1st LO is good, continue with “Check 2nd LO Signal at Sampler/Mixer.”

Check 2nd LO Signal at Sampler/Mixer

Check the 2nd LO signal at the pins identified in Table 8-3. Refer to the “A12 Reference Check” in Chapter 7, “Source Troubleshooting,” for analog bus and oscilloscope checks of the 2nd LO and waveform illustrations. Table 8-3 identifies the signal location at the samplers and the A12 assembly.

Table 8-3. 2nd LO Locations

Mnemonic	Description	Sampler Location	Signal Source
2nd LO 1	2nd LO (0 degrees)	A4/5/6 P1-11	A12P1-2, 32
2nd LO 2	2nd LO (-90 degrees)	A4/5/6 P1-4	A12P1-4, 34

If the 2nd LO is good at the sampler/mixer, the sampler/mixer assembly is faulty. Otherwise, troubleshoot the A12 assembly and associated signal path.

Accessories Troubleshooting

Use this procedure only if you have read Chapter 4, “Start Troubleshooting Here.” Follow the procedures in the order given, unless instructed otherwise.

Measurement failures can be divided into two categories:

- Failures which don’t affect the normal functioning of the analyzer but render incorrect measurement data.
- Failures which impede the normal functioning of the analyzer or prohibit the use of a feature.

This chapter addresses the first category of failures which are usually caused by the following:

- operator errors
- faulty calibration devices or connectors
- bad cables or adapters
- improper calibration techniques

These failures are checked using the following procedures:

- “Inspect the Accessories”
- “Inspect the Error Terms”

Assembly Replacement Sequence

The following steps show the sequence to replace an assembly in an HP 8753D Network Analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Inspect the Accessories

Inspect the Test Port Connectors and Calibration Devices

1. Check for damage to the mating contacts of the test port center conductors and loose connector bulkheads.
2. Inspect the calibration kit devices for bent or broken center conductors and other physical damage. Refer to the calibration kit operating and service manual for information on gaging and inspecting the device connectors.
If any calibration device is obviously damaged or out of mechanical tolerance, replace the device.

Inspect the Error Terms

Error terms are a measure of a “system”: a network analyzer, calibration kit, and any cables used. As required, refer to Chapter 11, “Error Terms” for the following:

- The specific measurement calibration procedure used to generate the error terms.
- The routines required to extract error terms from the instrument.
- Typical error term data.

Use Table 9-1 to cross-reference error term data to system faults.

Table 9-1. Components Related to Specific Error Terms

Component	Directivity	Source Match	Reflection Tracking	Isolation	Load Match	Transmission Tracking
Calibration Kit						
load	X					
open/short	X	X				
Analyzer						
sampler			X	X		X
A10 digital IF				X		
test port connectors	X	X	X	X	X	X
External cables					X	X

If you detect problems using error term analysis, use the following approach to isolate the fault:

1. Check the cable by examining the load match and transmission tracking terms. If those terms are incorrect, go to “Cable Test.”
2. Verify the calibration kit devices:

Loads: If the directivity error term looks good, the load and the test port are good. If directivity looks bad, connect the same load on the other test port and measure its directivity. If the second port looks bad, as if the problem had shifted with the load, replace the load. If the second port looks good, as if the load had not been the problem, troubleshoot the first port.

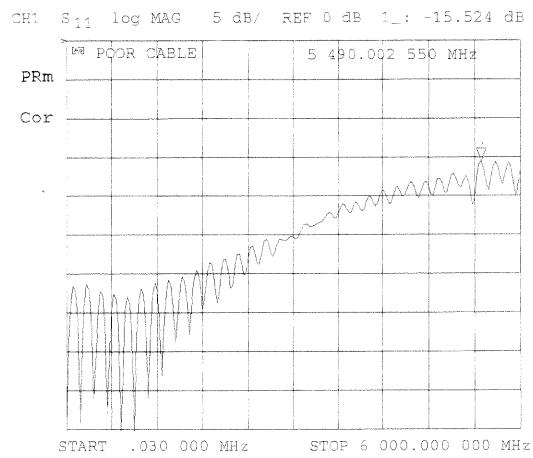
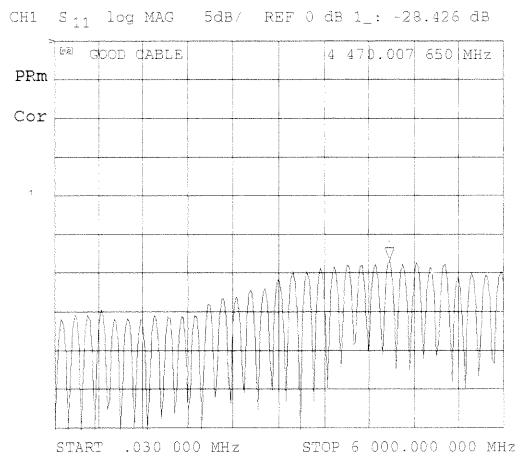
Shorts and opens: If the source match and reflection tracking terms look good, the shorts and the opens are good. If these terms look bad while the rest of the terms look good, proceed to “Verify Shorts and Opens.”

9-4 Accessories Troubleshooting

Cable Test

The load match error term is a good indicator of cable problems. You can further verify a faulty cable by measuring the reflection of the cable. Perform an S11 1-port calibration directly at port 1 (no cables). Then connect the suspect cable to port 1 and terminate the open end in 50 ohms.

Figure 9-1 shows the return loss trace of a good (left side) and faulty cable. Note that the important characteristic of a cable trace is its level (the good cable trace is much lower) not its regularity. Refer to the cable manual for return loss specifications.



sg642d

Figure 9-1. Typical Return Loss Traces of Good and Poor Cables

Verify Shorts and Opens

Substitute a known good short and open of the same connector type and sex as the short and open in question. If the devices are not from one of the standard calibration kits, refer to the *HP 8753D Network Analyzer User's Guide* for information on how to use the **MODIFY CAL KIT** function. Set aside the short and open that are causing the problem.

1. Perform an S11 1-port calibration using the good short and open. Then press **FORMAT SMITH CHART** to view the devices in Smith chart format.
2. Connect the good short to port 1. Press **[SCALE REF] ELECTRICAL DELAY** and turn the front panel knob to enter enough electrical delay so that the trace appears as a dot at the left side of the circle. (See Figure 9-2a, left.)

Replace the good short with the questionable short at port 1. The trace of the questionable short should appear very similar to the known good short.

3. Connect the good open to port 1. Press **[SCALE REF] ELECTRICAL DELAY** and turn the front panel knob to enter enough electrical delay so that the trace appears as a dot at the right side of the circle. (See Figure 9-2b, right.)

Replace the good open with the questionable open at port 1. The trace of the questionable open should appear very similar to the known good open.

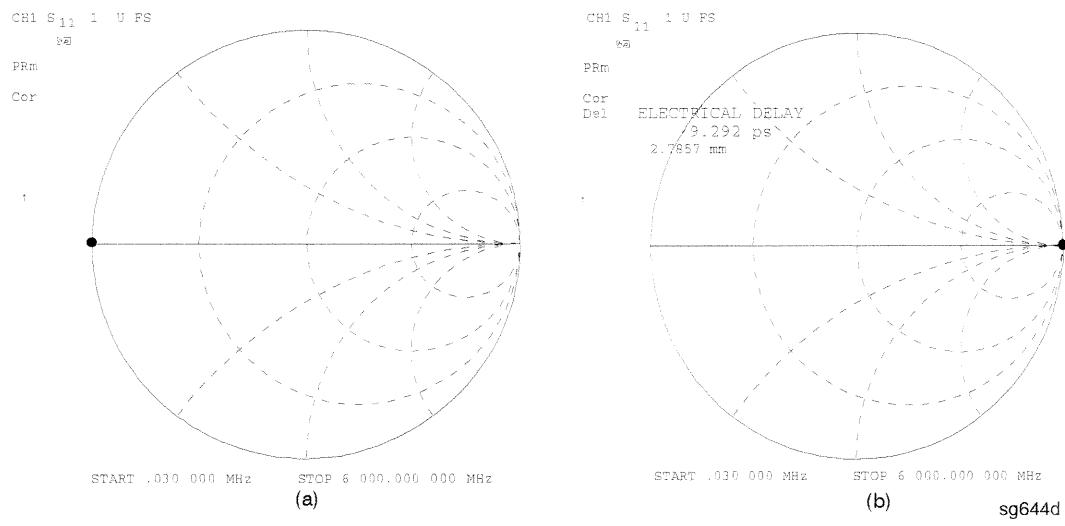


Figure 9-2. Typical Smith Chart Traces of Good Short (a) and Open (b)

10

Service Key Menus and Error Messages

Service Key Menus

These menus allow you to perform the following service functions:

- test
- verify
- adjust
- control
- troubleshoot

The menus are divided into two groups:

1. Internal Diagnostics
2. Service Features

When applicable, the HP-IB mnemonic is written in parentheses following the key. See HP-IB Service Mnemonic Definitions at the end of this section.

Error Messages

The displayed messages that pertain to service functions are also listed in this chapter to help you:

- Understand the message.
- Solve the problem.

Service Key Menus - Internal Diagnostics

The internal diagnostics menus are shown in Figure 10-1 and described in the following paragraphs. The following keys access the internal diagnostics menus:

- TESTS
- TEST OPTIONS
- SELF-DIAGNOSE

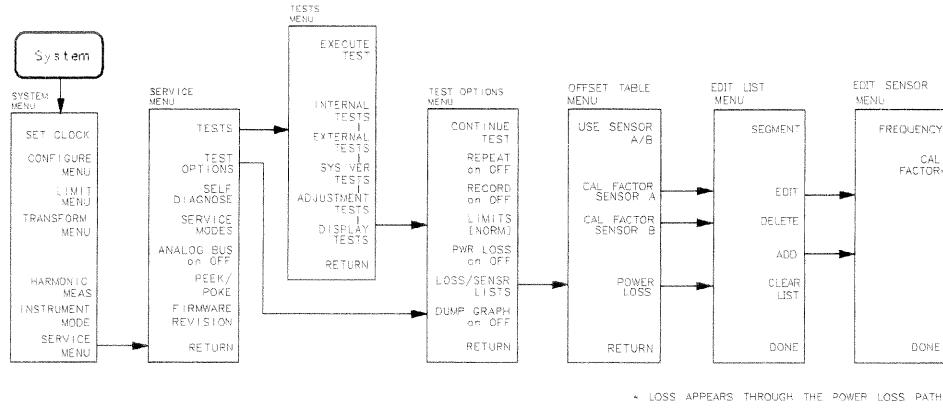


Figure 10-1. Internal Diagnostics Menus

Note

Throughout this service guide, these conventions are observed:

- **HARDKEYS** are labeled front panel keys
- **SOFTKEYS** are display defined keys (in the menus)
- (HP-IB COMMANDS) when applicable, follow the keystrokes in parentheses

10-2 Service Key Menus and Error Messages

Tests Menu

To access this menu, press **SYSTEM SERVICE MENU TESTS**.

TESTS (TEST [D]) accesses a menu that allows you to select or execute the service tests. The default is set to internal test 1.

Note Descriptions of tests in each of the categories are given under the heading *Test Descriptions* in the following pages.

The tests are divided by function into the following categories:

- Internal Tests (0–20)
- External Tests (21–26)
- System Verification Tests (27–43)
- Adjustment Tests (44–58)
- Display Tests (59–65)
- Test Patterns (66–80)

To access the first test in each category, press the category softkey. To access the other tests, use the numeric keypad, step keys or front panel knob. The test number, name, and status abbreviation will be displayed in the active entry area of the display.

Table 10-1 shows the test status abbreviation that appears on the display, its definition, and the equivalent HP-IB code. The HP-IB command to output the test status of the most recently executed test is OUTPTESS. For more information, refer to “HP-IB Service Mnemonic Definitions” located at the end of this chapter.

Table 10-1. Test Status Terms

Display Abbreviation	Definition	HP-IB Code
PASS	PASS	0
FAIL	FAIL	1
-IP-	IN PROGRESS	2
(NA)	NOT AVAILABLE	3
-ND-	NOT DONE	4
DONE	DONE	5

EXECUTE TEST (EXET) runs the selected test and may display these softkeys:

CONTINUE (TESR1) continues the selected test.

YES (TESR2) alters correction constants during adjustment tests.

NEXT (TESR4) displays the next choice.

SELECT (TESR6) chooses the option indicated.

ABORT (TESR8) terminates the test and returns to the tests menu.

INTERNAL TESTS evaluates the analyzer’s internal operation. These tests are completely internal and do not require external connections or user interaction.

EXTERNAL TESTS evaluate the analyzer’s external operation. These additional tests require some user interaction (such as keystrokes).

10-4 Service Key Menus and Error Messages

SYS VER TESTS	verifies the analyzer system operation by examining the contents of the measurement calibration arrays. The procedure is in the "System Verification and Performance Tests" chapter. Information about the calibration arrays is provided in the "Error Terms" chapter.
ADJUSTMENT TESTS	generates and stores the correction constants. For more information, refer to the "Adjustments" chapter.
DISPLAY TESTS	checks for correct operation of the display and GSP board.

Test Options Menu

To access this menu, press **SYSTEM SERVICE MENU TEST OPTIONS**.

TEST OPTIONS	accesses softkeys that affect the way tests (routines) run, or supply necessary additional data.
CONTINUE TEST (TESR1)	resumes the test from where it was stopped.
REPEAT on OFF (TO2)	toggles the repeat function on and off. When the function is ON, the selected test will run 10,000 times unless you press any key to stop it. The analyzer shows the current number of passes and fails.
RECORD on OFF (TO1)	toggles the record function on and off. When the function is ON, certain test results are sent to a printer via HP-IB. This is especially useful for correction constants. The instrument must be in system controller mode or pass control mode to print. (Refer to the "Printing, Plotting, and Saving Measurement Results" chapter in the <i>HP 8753D User's Guide</i> .)
LIMITS [NORM/SPCL]	selects either NORMal or SPeCiaL (tighter) limits for the Operator's Check. The SPCL limits are useful for a guard band.
POWER LOSS (POWLLIST)	accesses the following Edit List menu to allow modification of the external power loss data table.

LOSS/SENSR LISTS

accesses the power loss/sensor lists menu:

USE SENSOR A/B selects the A or B power sensor calibration factor list for use in power meter calibration measurements.

CAL FACTOR SENSOR A (CALFSENA) accesses the Edit List menu to allow modification of the calibration data table for power sensor A.

CAL FACTOR SENSOR B (CALFSENB) accesses the Edit List menu to allow modification of the calibration data table for power sensor B.

POWER LOSS (POWLLIST) accesses the Edit List menu to allow modification of the external power loss data table that corrects coupled-arm power loss when a directional coupler samples the RF output.

Edit List Menu To access this menu, press **SYSTEM SERVICE MENU**

TEST OPTIONS LOSS/SENSR LISTS and then press one of the following:

CAL FACTOR SENSOR A or **CAL FACTOR SENSOR B** or **POWER LOSS**.

SEGMENT

selects a segment (frequency point) to be edited, deleted from, or added to the current data table. Works with the entry controls.

EDIT (SEDI[D])

allows modification of frequency, cal factor and loss values previously entered in the current data table.

DELETE (SDEL)

deletes frequency, cal factor and loss values previously entered in the current data table.

ADD (SADD)

adds new frequency, cal factor and loss values to the current data table up to a maximum of 12 segments (frequency points, PTS).

CLEAR LIST (CLEL)

deletes the entire current data table (or list) when **YES** is pressed. Press **NO** to avoid deletion.

DONE (EDITDONE)

returns to the previous menu.

10-6 Service Key Menus and Error Messages

Self Diagnose Softkey

You can access the self diagnosis function by pressing, **SYSTEM SERVICE MENU SELF DIAGNOSE**. This function examines, in order, the pass/fail status of all internal tests and displays **NO FAILURE FOUND** if no tests have failed.

If a failure is detected, the routine displays the assembly or assemblies most probably faulty and assigns a failure probability factor to each assembly.

Test Descriptions

The analyzer has up to 80 routines that test, verify, and adjust the instrument. This section describes those tests.

Internal Tests

This group of tests runs without external connections or operator interaction. All return a PASS or FAIL condition. All of these tests run on power-up and PRESET except as noted.

- 0 **ALL INT.** Runs only when selected. It consists of internal tests 3-11, 13-16, and 20. Use the front panel knob to scroll through the tests and see which failed. If all pass, the test displays a PASS status. Each test in the subset retains its own test status.
- 1 **PRESET.** Runs the following subset of internal tests: first, the ROM/RAM tests 2, 3, and 4; then tests 5 through 11, 14, 15, and 16. If any of these tests fail, this test returns a FAIL status. Use the front panel knob to scroll through the tests and see which failed. If all pass, this test displays a PASS status. Each test in the subset retains its own test status. This same subset is available over HP-IB as "TST?". It is not performed upon remote preset.
- 2 **ROM.** Part of the ROM/RAM tests and cannot be run separately. Refer to the "Digital Control Troubleshooting" chapter for more information.
- 3 **CMOS RAM.** Verifies the A9 CPU CMOS (long-term) memory with a non-destructive write/read pattern. A destructive version that writes over stored data is shown in Table 10-2.

- 4 **Main DRAM.** Verifies the A9 CPU main memory (DRAM) with a non-destructive write/read test pattern. A destructive version is shown in Table 10-2. These tests, internal tests 2 through 4, are normally run at preset and power-on. However, a jumper on the A9 CPU assembly, illustrated in Figure 10-2, can be set in one of five positions with the following results:

Table 10-2. Descriptions of Jumper Positions

Jumper Position	Position No	Result
ALTER	1	With the jumper in this right position, correction constants can be altered, (updated) during adjustment procedures. The altered correction constants are stored in EEPROM, replacing previously stored correction constants.
CMOS	2	This destructive version of the CMOS RAM test (internal test 3) continuously writes over information stored there.
DRAM	3	This destructive version of the main DRAM test (internal test 4) continuously writes over information stored there.
SKIP	4	For factory use only.
NORMAL	5	The left position is the normal operation position.

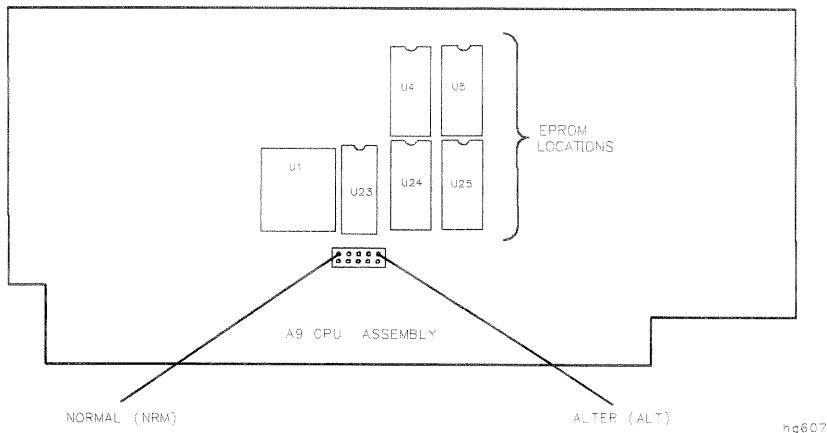


Figure 10-2. Jumper Positions on the A9 CPU

10-8 Service Key Menus and Error Messages

For additional information, see "Internal Tests" (near the front of this section) and the "Digital Control Troubleshooting" chapter.

- 5 **DSP Wr/Rd.** Verifies the ability of the main processor and the DSP (digital signal processor), both on the A9 CPU assembly, to communicate with each other through DRAM. This also verifies that programs can be loaded to the DSP, and that most of the main RAM access circuits operate correctly.
- 6 **DSP RAM.** Verifies the A9 CPU RAM associated with the digital signal processor by using a write/read pattern.
- 7 **DSP ALU.** Verifies the A9 CPU high-speed math processing portions of the digital signal processor.
- 8 **DSP Intrpt.** Tests the ability of the A9 CPU digital signal processor to respond to interrupts from the A10 digital IF ADC.
- 9 **DIF Control.** Tests the ability of the A9 CPU main processor to write/read to the control latches on the A10 digital IF.
- 10 **DIF Counter.** Tests the ability of the A9 CPU main processor to write/read to the triple divider on the A10 CPU. It tests the A9 CPU data buffers and A10 digital IF, the 4 MHz clock from the A12 reference.
- 11 **DSP Control.** Tests the ability of the A9 CPU digital signal processor to write to the control latches on the A10 digital IF. Feedback is verified by the main processor. It primarily tests the A10 digital IF, but failures may be caused by the A9 CPU.
- 12 **Fr Pan Wr/Rd.** Tests the ability of the A9 CPU main processor to write/read to the front panel processor. It tests the A2 front panel interface and processor, and A9 CPU data buffering and address decoding. (See also tests 23 and 24 below.) This runs only when selected.
- 13 **Rear Panel.** Tests the ability of the A9 CPU main processor to write/read to the rear panel control elements. It tests the A16 rear panel, and A9 CPU data buffering and address decoding. (It does not test the HP-IB interface; for that see the *HP-IB Programming Guide*.) This runs only when selected or with ALL INTERNAL.
- 14 **Post Reg.** Polls the status register of the A8 post-regulator, and flags these conditions: heat sink too hot, inadequate air flow, or post-regulated supply shutdown.

- 15 **Frac N Cont.** Tests the ability of the A9 CPU main processor to write/read to the control element on the A14 fractional-N (digital) assembly. The control element must be functioning, and the fractional-N VCO must be oscillating (although not necessarily phase-locked) to pass.
- 16 **Sweep Trig.** Tests the sweep trigger (L SWP) line from the A14 fractional-N to the A10 digital IF. The receiver with the sweep synchronizes L SWP.
- 17 **ADC Lin.** It tests the linearity of the A10 digital IF ADC using the built-in ramp generator. The test generates a histogram of the ADC linearity, where each data point represents the relative “width” of a particular ADC code. Ideally, all codes have the same width; different widths correspond to non-linearities.
- 18 **ADC Ofs.** This runs only when selected. It tests the ability of the offset DAC, on the A10 digital IF, to apply a bias offset to the IF signals before the ADC input. This runs only when selected.
- 19 **ABUS Test.** Tests analog bus accuracy, by measuring several analog bus reference voltages (all nodes from the A10 digital IF). This runs only when selected.
- 20 **FN Count.** Uses the internal counter to count the A14 fractional-N VCO frequency (120 to 240 MHz) and the divided fractional-N frequency (100 kHz). It requires the 100 kHz signal from A12 and the counter gate signal from A10 to pass.

10-10 Service Key Menus and Error Messages

External Tests

These tests require either external equipment and connections or operator interaction of some kind to run. Tests 30 and 60 are comprehensive front panel checks, more complete than test 12, that checks the front panel keys and knob entry.

- 21 **Port 1 Op Chk.** Part of the “Operator’s Check” procedure, located in the “Start Troubleshooting” chapter. The procedure requires the external connection of a short to PORT 1.
- 22 **Port 2 Op Chk.** Same as 21, but tests PORT 2.
- 23 **Fr Pan Seq.** Tests the front panel knob entry and all A1 front panel keys, as well as the front panel microprocessor on the A2 assembly. It prompts the user to rotate the front panel knob, then press each key in an ordered sequence. It continues to the next prompt only if the current prompt is correctly satisfied.
- 24 **Fr Pan Diag.** Similar to 23 above, but the user rotates the front panel knob or presses the keys in any order. This test displays the command the instrument received.
- 25 **ADC Hist.** Factory use only.
- 26 **Source Ex.** Factory use only.

System Verification Tests

These tests apply mainly to system-level, error-corrected verification and troubleshooting. Tests 27 to 31 are associated with the system verification procedure, documented in the “System Verification and Performance Tests” chapter. Tests 32 to 43 facilitate examining the calibration coefficient arrays (error terms) resulting from a measurement calibration; refer to the “Error Terms” chapter for details.

- 27 **Sys Ver Init.** Recalls the initialization state for system verification from an HP 8753D verification disk, in preparation for a measurement calibration. It must be done before service internal tests 28, 29, 30 or 31 are performed.
- 28 **Ver Dev 1.** Recalls verification limits from disk for verification device #1 in all applicable S-parameter measurements. It performs pass/fail limit testing of the current measurement.
- 29 **Ver Dev 2.** Same as 28 above for device #2.
- 30 **Ver Dev 3.** Same as 28 above for device #3.
- 31 **Ver Dev 4.** Same as 28 above for device #4.
- 32-43 **Cal Coef 1-12.** Copies error term data from a measurement calibration array to display memory. A measurement calibration must be complete and active. The definition of calibration arrays depends on the current calibration type. After execution, the memory is automatically displayed. Refer to the “Error Term” chapter for details.

10-12 Service Key Menus and Error Messages

Adjustment Tests

The tests without asterisks are used in the procedures located in the “Adjustments” chapter of this manual, except as noted.

- 44 ***Source Def.** Writes default correction constants for rudimentary source power accuracy. Use this test before running test 47, below.
- 45 ***Pretune Def.** Writes default correction constants for rudimentary phase lock pretuning accuracy. Use this test before running test 48, below.
- 46 **ABUS Cor.** Measures three fixed voltages on the ABUS, and generates new correction constants for ABUS amplitude accuracy in both high resolution and low resolution modes. Use this test before running test 48, below.
- 47 **Source Cor.** Measures source output power accuracy, flatness, and linearity against an external power meter via HP-IB to generate new correction constants. Run tests 44, 45, 46, and 48 first.
- 48 **Pretune Cor.** Generates source pretune values for proper phase-locked loop operation. Run tests 44, 45, and 46 first.
- 49 **Intensity Cor.** Stores the current values of the intensity adjustments under **[DISPLAY]** for recall of display intensity values at power-on.
- 50 **Disp 2 Ex.** Not used in “Adjustments.” Writes the “secondary test pattern” to the display for adjustments. Press **[PRESET]** to exit this routine.
- 51 **IF Step Cor.** Measures the gain of the IF amplifiers (A and B only) located on the A10 digital IF, to determine the correction constants for absolute amplitude accuracy. It provides smooth dynamic accuracy and absolute amplitude accuracy in the –30 dBm input power region.
- 52 **ADC Ofs Cor.** Measures the A10 Digital IF ADC linearity characteristics, using an internal ramp generator, and stores values for the optimal operating region. During measurement, IF signals are centered in the optimal region to improve low-level dynamic accuracy.
- 53 **Sampler Cor.** Measures the absolute amplitude response of the R sampler against an external power meter via HP-IB, then compares A and B, (magnitude and phase), against R. It improves the R input accuracy and A/B/R tracking.

- 54 **Cav Osc Cor.** Calculates the frequency of the cavity oscillator and the instrument temperature for effective spur avoidance.
- 55 **Serial Cor.** Stores the serial number (input by the user in the Display Title menu) in EEPROM. This routine will not overwrite an existing serial number.
- 56 **Option Cor.** Stores the option keyword (required for Option 002, 006, 010 or any combination).
- 57 **Cal Kit Def.** Not used.
- 58 **Init EEPROM.** This test initializes certain EEPROM addresses to zeros and resets the display intensity correction constants to the default values. Also, the test will not alter the serial number and correction constants for Option 002, 006, and 010.

10-14 Service Key Menus and Error Messages

Display Tests

These tests do not return a PASS/FAIL condition. All six amber front panel LEDs will turn off if the test passes. The display will be blank; press **[PRESET]** to exit the test. If any of the six LEDs remain on, the test has failed.

- 59 **Disp/cpu com.** Checks to confirm that the CPU can communicate with the A19 GSP board. The CPU writes all zeros, all ones, and then a walking one pattern to the GSP and reads them back. If the test fails, the CPU repeats the walking 1 pattern until **[PRESET]** is pressed.
- 60 **DRAM cell.** Tests the DRAM on A19 by writing a test pattern to the DRAM and then verifying that it can be read back.
- 61 **Main VRAM.** Tests the VRAM by writing all zeros to one location in each bank and then writing all ones to one location in each bank. Finally a walking one pattern is written to one location in each bank.
- 62 **VRAM bank.** Tests all the cells in each of the 4 VRAM banks.
- 63 **VRAM/video.** Verifies that the GSP is able to successfully perform both write and read shift register transfers. It also checks the video signals LHSYNC, LVSYNC, and LBLANK to verify that they are active and toggling.
- 64 **RGB outputs.** Confirms that the analog video signals are correct and it verifies their functionality.
- 65 **Inten DAC.** Verifies that the intensity DAC can be set both low and high.

Test Patterns

Test patterns are used in the factory for display adjustments, diagnostics, and troubleshooting, but they are not used for field service. Test patterns are executed by entering the test number (66 through 80), then pressing **EXECUTE TEST CONTINUE**. The test pattern will be displayed and the softkey labels blanked. To exit the test pattern and return the softkey labels, press softkey 8 (bottom softkey). The following is a description of the test patterns.

- 66 **Test Pat 1.** Displays an all white screen for verifying the light output of the A18 display and checks for color purity. In this, and other solid test patterns, an extremely thin full-screen horizontal line will be seen about 1/4 screen height from the bottom. This condition is characteristic of the display and does not indicate any problem.
- 67-69 **Test Pat 2-4.** Displays a red, green, and blue pattern for verifying the color purity of the display and also the ability to independently control each gun color. If the purity of the displayed test pattern is a problem, it usually indicates that the face of the display needs to be de-gaused (de-magnetized). If the purity is bad, cycling the power a few times may cure the problem. If this does not work, a commercially available de-magnetizer must be used.
- 70 **Test Pat 5.** Displays a 16-step gray scale for verifying that the palette chip on the A19 GSP board can produce 16 different amplitudes of color (in this case, white). This pattern is also very useful when using an oscilloscope for troubleshooting. The staircase pattern it produces will quickly show missing or stuck data bits.
- 71 **Test Pat 6.** Displays a 3-step gray scale pattern for adjusting the background level (or 0 step) so that the first bar is not visible, and the second bar is just barely visible. This pattern consists of the first three gray scale bars of the 16-step gray scale.
- 72 **Test Pat 7.** Displays a convergence pattern for measuring the accuracy of the color convergence. It is mainly for use by the factory, since convergence cannot be adjusted in the field.
- 73-74 **Test Pat 8-9.** Displays crosshatch and inverse crosshatch patterns for testing color convergence, linearity, alignment, and high voltage regulation, in the factory only. No field adjustments are possible.

10.16 Service Key Menus and Error Messages

- 75 **Test Pat 10.** Displays an H pattern for checking the focus of the display. Under normal conditions, this should never need to be adjusted. However, it is possible to adjust it by accessing the focus control adjustment at the left rear of the display. See the "Adjustments" chapter.
- 76 **Test Pat 11.** Verifies the functionality of the pixel stretching circuit of the A19 GSP board. Under normal conditions, this pattern should appear all white. If a failure occurs in the pixel stretching circuit, the pattern will consist of 16 alternating white and gray vertical stripes. Suspect problems with the STRETCH line and LFIRSTPIX.
- 77 **Test Pat 12.** Displays a repeating gray scale for troubleshooting, using an oscilloscope. It is similar to the 16 step gray scale but is repeated 32 times across the screen. Each of the 3 outputs of the video palette will then show 32 ramps (instead of one staircase) between each horizontal sync pulse. This pattern is used to troubleshoot the pixel processing circuit of the A19 GSP board.
- 78 **Test Pat 13.** Displays a color rainbow pattern for showing the ability of the A19 GSP board to display 15 colors plus white. The numbers written below each bar indicate the tint number used to produce that bar (0 & 100=pure red, 33=pure green, 67=pure blue).
- 79 **Test Pat 14.** Displays a character set for showing the user all the different types and sizes of characters available. Three sets of characters are drawn in each of the three character sizes. 125 characters of each size are displayed. Characters 0 and 3 cannot be drawn and several others are really control characters (such as carriage return and line feed).
- 80 **Test Pat 15.** Displays a bandwidth pattern for verifying the bandwidth of the display. It consists of multiple alternating white and black vertical stripes. Each stripe should be clearly visible. A limited bandwidth would smear these lines together. This adjustment can be performed in the factory only.

Service Key Menus - Service Features

The service feature menus are shown in Figure 10-3 and described in the following paragraphs. The following keys access the service feature menus:

- SERVICE MODES
- ANALOG BUS on OFF
- PEEK/POKE
- FIRMWARE REVISION

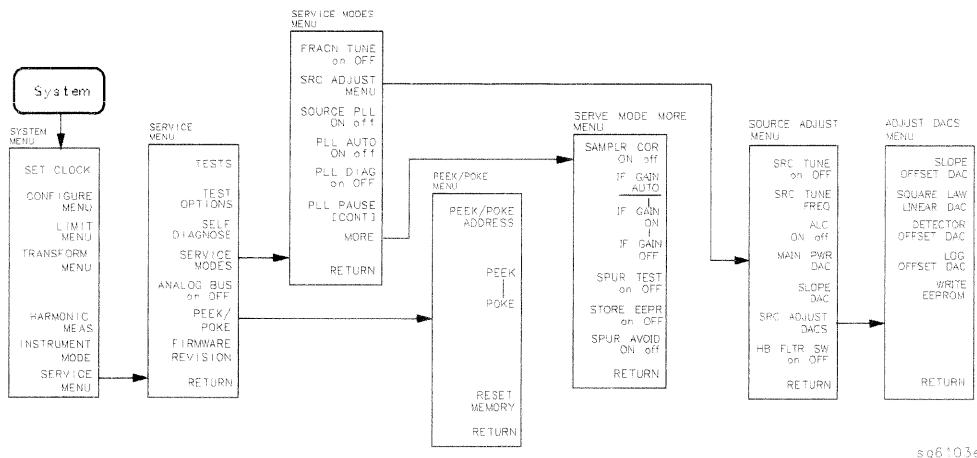


Figure 10-3. Service Feature Menus

Service Modes Menu

To access this menu, press: **SYSTEM SERVICE MENU SERVICE MODES**

SERVICE MODES allows you to control and monitor various circuits for troubleshooting.

FRACN TUNE on OFF (SM1) tests the A13 and A14 fractional-N circuits. It allows you to directly control and monitor the output frequency of the fractional-N synthesizer (10 MHz to 60 MHz). Set the instrument to CW sweep mode and then set FRACN TUNE ON.

10.18 Service Key Menus and Error Messages

Change frequencies with the front panel keys or knob. The output of the A14 assembly can be checked at A14J1 HI OUT (in high band) or A14J2 LO OUT (in low band) with an oscilloscope, a frequency counter, or a spectrum analyzer. Signal jumps and changes in shape at 20 MHz and 30 MHz when tuning up in frequency, and at 29.2 MHz and 15 MHz when tuning down, are due to switching of the digital divider. This mode can be used with the SRC TUNE mode as described in “Source Troubleshooting” chapter.

SRC ADJUST MENU

accesses the functions that allow you to adjust the source:

SRC TUNE on OFF tests the preture functions of the phase lock and source assemblies. Use the entry controls to set test port output to any frequency from 300 kHz to 6 GHz. When in this mode:

- Set analyzer to CW frequency before pressing **SRC TUNE ON**.
- Test port output is 1 to 6 MHz above indicated (entered) frequency.
- Instrument does not attempt to phase lock.
- Residual FM increases.

SRC TUNE FREQ allow you to change the source tune frequency.

ALC ON off toggles the automatic leveling control (ALC) on and off.

MAIN PWR DAC

SLOPE DAC

SRC ADJUST DACS

HB FLTR SW on OFF

SOURCE PLL ON off
(SM3)

With this mode switched OFF, the source stays in the pretune mode and does not attempt to complete the phase lock sequence. Also, all phase lock error messages are disabled. The fractional-N circuits and the receiver operate normally. Therefore, the instrument sweeps, but the source is being driven by the pretune DAC in a stair-stepped fashion.

PLL AUTO ON off (SM4)

Automatically attempts to determine new pretune values when the instrument encounters phase lock problems (for example, "harmonic skip"). With PLL AUTO OFF the frequencies and voltages do not change, like when they are attempting to determine new pretune values, so troubleshooting the phase-locked loop circuits is more convenient. This function may also be turned off to avoid pretune calibration errors in applications where there is a limited frequency response in the R (reference) channel. For example, in a high power test application, using band limited filters for R channel phase locking.

PLL DIAG on OFF (SM5)

displays a phase lock sequence at the beginning of each band. This sequence normally occurs very rapidly, making it difficult to troubleshoot phase lock problems. Switching this mode ON slows the process down, allowing you to inspect the steps of the phase lock sequence (pretune, acquire, and track) by pausing at each step. The steps are indicated on the display, along with the channel (C1 or C2) and band number (B1 through B13).

This mode can be used with PLL PAUSE to halt the process at any step. It can also be used with the analog bus counter.

PLL PAUSE

used only with PLL DIAG mode. CONT indicates that it will continuously cycle through all steps of the phase lock sequence. PAUSE holds it at any step of interest. This mode is useful for troubleshooting phase-locked loop problems.

MORE

Accesses the service modes more menu listed below.

10-20 Service Key Menus and Error Messages

Service Modes More Menu

To access this menu, press **SYSTEM** SERVICE MENU SERVICE MODES MORE.

SAMPLER COR ON off (SM6)	Toggles the sampler correction routine ON, for normal operation, or OFF, for diagnosis or adjustment purposes.
IF GAIN AUTO	Normal operating condition and works in conjunction with IF GAIN ON and OFF. The A10 assembly includes a switchable attenuator section and an amplifier that amplifies low-level 4 kHz IF signals (for A and B inputs only). This mode allows the A10 IF section to automatically determine if the attenuator should be switched in or out. The switch occurs when the A or B input signal is approximately -30 dBm.
IF GAIN ON	Locks out the A10 IF attenuator sections for checking the A10 IF gain amplifier circuits, regardless of the amplitude of the A or B IF signal. Switches out both the A and B attenuation circuits; they cannot be switched independently. Be aware that input signal levels above -30 dBm at the sampler input will saturate the ADC and cause measurement errors.
IF GAIN OFF	Switches in both of the A10 IF attenuators for checking the A10 IF gain amplifier circuits. Small input signals will appear noisy, and raise the apparent noise floor of the instrument.
SPUR TEST on OFF (SM7)	For factory use only.
STORE EEPROM on OFF	Allows you to store the correction constants that reside in non-volatile memory (EEPROM) onto a disk. Correction constants improve instrument performance by compensating for specific operating variations due to hardware limitations (refer to the "Adjustments" chapter). Having this information on disk is useful as a backup, in case the constants are lost (due to a CPU board failure). Without a disk backup the correction constants can be regenerated

SPUR AVOID ON off (SM8)	manually, although the procedures are more time consuming.
	Offsets the frequency of both the A3 YIG oscillator and the A3 cavity oscillator to avoid spurs which cannot otherwise be filtered out. SPUR AVOID OFF allows examination of these spurs for service.
ANALOG BUS on OFF (ANAB)	enables and disables the analog bus, described below. Use it with the analog in menu, (a description of this menu follows).

Analog Bus

To access the analog bus, press **SYSTEM** SERVICE MENU ANALOG BUS ON.

Description of the Analog Bus

The analog bus is a single multiplexed line that networks 31 nodes within the instrument. It can be controlled from the front panel, or through HP-IB, to make voltage and frequency measurements just like a voltmeter, oscilloscope, or frequency counter. The next few paragraphs provide general information about the structure and operation of the analog bus. See "Analog Bus Nodes," below, for a description of each individual node. Refer to the "Overall Block Diagram," in the "Start Troubleshooting" chapter, to see where the nodes are located in the instrument.

The analog bus consists of a source section and a receiver section. The source can be the following:

- any one of the 31 nodes described in "Analog Bus Nodes"
- the A14 fractional-N VCO
- the A14 fractional-N VCO divided down to 100 kHz

The receiver portion can be the following:

- the main ADC
- the frequency counter

When analog bus traces are displayed, frequency is the x-axis. For a linear x-axis in time, switch to CW time mode (or sweep a single band).

The Main ADC

The main ADC is located on the A10 digital IF assembly and makes voltage measurements in two ranges. See “**RESOLUTION**,” under “Analog In Menu.”

The Frequency Counter

The frequency counter is located on the A14 assembly and can count one of three sources:

- selected analog bus node
- A14 fractional-N VCO (FRAC N)
- A14 fractional-N VCO divided down to 100 kHz (DIV FRAC N) (frequency range is 100 kHz to 16 MHz)

The counts are triggered by the phase lock cycle; one at each preture, acquire, and track for each bandswitch. (The service mode, SOURCE PLL, must be ON for the counter to be updated at each bandswitch.) The counter works in swept modes or in CW mode. It can be used in conjunction with **SERVICE MODES** for troubleshooting phase lock and source problems.

To read the counter over HP-IB, use the command OUTPCNTR.

Notes

- The display and marker units (U) correspond to volts.
- Nodes 17 (1st IF) and 24 (2nd LO) are unreliable above 1 MHz.
- About 0.750 MHz is a typical counter reading with no AC signal present.
- Anything occurring during bandswitches is not visible.
- Fast-moving waveforms may be sensitive to sweep time.
- The analog bus input impedance is about 50 K ohms.
- Waveforms up to approximately 200 Hz can be reproduced.

Analog In Menu

Select this menu to monitor voltage and frequency nodes, using the analog bus and internal counter, as explained below.

To switch on the analog bus and access the analog in menu, press:

SYSTEM SERVICE MENU ANALOG BUS ON [MEAS] ANALOG IN .

The **RESOLUTION [LOW]** key toggles between low and high resolution.

Resolution	Maximum Signal	Minimum Signal
LOW	+ 0.5 V	- 0.5 V
HIGH	+ 10 V	- 10 V

AUX OUT on OFF allows you to monitor the analog bus nodes (except nodes 1, 2, 3, 4, 9, 10, 12) with external equipment (oscilloscope, voltmeter, etc.). To do this, connect the equipment to the AUX INPUT BNC connector on the rear panel, and press **AUX OUT**, until **ON** is highlighted.

Caution To prevent damage to the analyzer, first connect the signal to the rear panel AUX INPUT, and then switch the function ON.

COUNTER: OFF switches the internal counter off and removes the counter display from the display. The counter can be switched on with one of the next three keys. (Note: Using the counter slows the sweep.) The counter bandwidth is 16 MHz unless otherwise noted for a specific node.

Note OUTPCNTR is the HP-IB command to output the counter's frequency data.

ANALOG BUS	switches the counter to monitor the analog bus.
FRAC N	switches the counter to monitor the A14 fractional-N VCO frequency at the node shown on the “Overall Block Diagram,” in the “Start Troubleshooting” chapter.
DIV FRAC N	switches the counter to monitor the A14 fractional-N VCO frequency after it has been divided down to 100 kHz for phase locking the VCO.

Analog Bus Nodes

The following paragraphs describe the 31 analog bus nodes. The nodes are listed in numerical order and are grouped by assembly. Refer to the “Overall Block Diagram” for node locations.

A3 Source

To observe six of the eight A3 analog bus nodes (not node 5 or 8), perform Step A3 to set up a power sweep on the analog bus. Then follow the node specific instructions.

Step A3.

Press:

PRESET
SYSTEM SERVICE MENU ANALOG BUS ON
MEAS ANALOG IN
FORMAT MORE REAL
MENU CW FREQ ③ G/n SWEEP TYPE MENU POWER SWEEP
START -15 x1
STOP 10 x1

Node 1 Mn Pwr DAC (main power DAC)

Perform step A3, above, to set up a power sweep on the analog bus. Then press **MEAS ANALOG IN 1 x1 SCALE REF AUTO SCALE**.

Node 1 is the output of the main power DAC. It sets the reference voltage to the ALC loop. At normal operation, this node should read approximately -4 volts at 0 dBm with a slope of about -150 mV/dB. This corresponds to approximately 4 volts from -15 to +10 dBm.

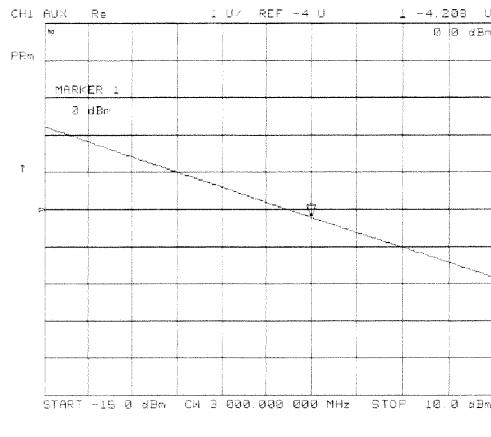


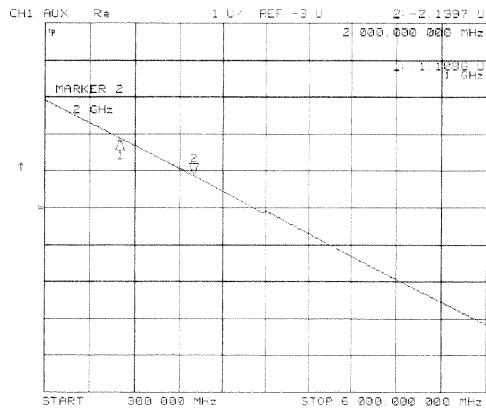
Figure 10-4. Analog Bus Node 1

Node 2 Src 1V/GHz (source 1 volt per GHz)

Press the following to view analog bus node 2:

[PRESET] [START] [3] [0] [k/m]
[SYSTEM] SERVICE MENU ANALOG BUS ON
[MEAS] ANALOG IN [2] [x1]
[FORMAT] MORE REAL
[SCALE REF] AUTO SCALE

Node 2 measures the voltage on the internal voltage controlled oscillator. Or, in normal operation, it should read –1V/GHz.



sg6263d

Figure 10-5. Analog Bus Node 2

Node 3 Amp Id (amplifier current)

Press the following keys to view analog node 3:

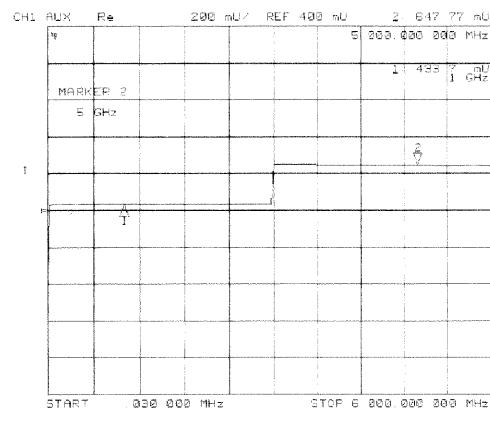
[PRESET] [SYSTEM] SERVICE MENU ANALOG BUS ON
[MEAS] ANALOG IN 3 [x1]
[FORMAT] MORE REAL
[SCALE REF] AUTO SCALE

Node 3 measures the current that goes to the main IF amplifier. At normal operation this node should read about:

15 mA from 30 kHz to 299 kHz

130 mA from 300 kHz to 3 GHz

500 mA from 3 GHz to 6 GHz



sg6264d

Figure 10-6. Analog Bus Node 3

Node 4 Det (detects RF OUT power level)

Perform step A3, described previously, to set up a power sweep on the analog bus. Then press [MEAS] ANALOG IN 4 x1 SCALE REF AUTO SCALE.

Node 4 detects power that is coupled and detected from the RF OUT arm to the ALC loop. Note that the voltage exponentially follows the power level inversely. Flat segments indicate ALC saturation and should not occur between –85 dBm and +10 dBm.

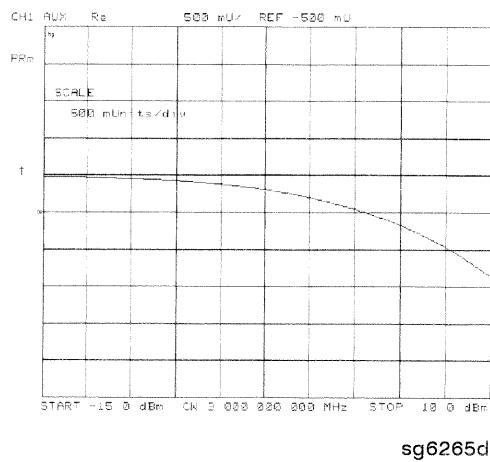


Figure 10-7. Analog Bus Node 4

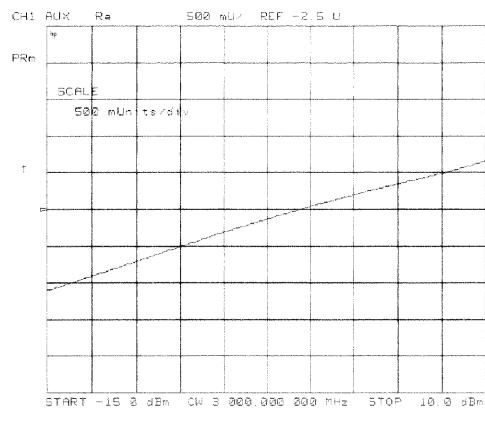
Node 5 Temp (temperature sensor)

This node registers the temperature of the cavity oscillator which must be known for effective spur avoidance. The sensitivity is 10 mV/ $^{\circ}$ C. The oscillator changes frequency slightly as its temperature changes. This sensor indicates the temperature so that the frequency can be predicted.

Node 6 Integ (ALC leveling integrator output)

Perform step A3, above, to set up a power sweep on the analog bus. Then press **MEAS ANALOG IN 6 x1 SCALE REF AUTO SCALE**.

Node 6 displays the output of the summing circuit in the ALC loop. Absolute voltage level variations are normal. When node 6 goes above 0 volts, the ALC saturation is indicated.



sg6266d

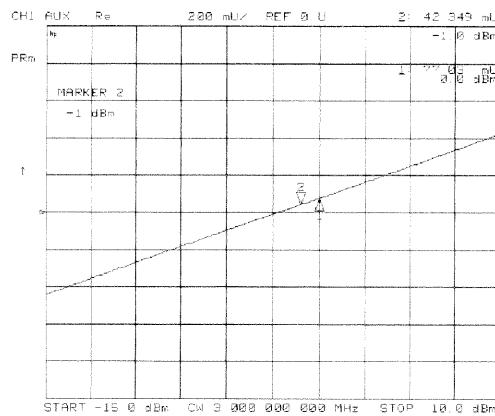
Figure 10-8. Analog Bus Node 6

Node 7 Log (log amplifier output detector)

Perform step A3, above, to set up a power sweep on the analog bus. Then press
MEAS ANALOG IN 7 x1 SCALE REF AUTO SCALE.

Node 7 displays the output of a logger circuit in the ALC loop. The trace should be a linear ramp with a slope of 33 mv/dB with approximately 0 volts at -3 dBm. Absolute voltage level variations are normal. Flat segments indicate ALC saturation and should not occur between -15 dBm and +10 dBm.

The proper waveform at node 7 indicates that the circuits in the A3 source ALC loop are normal and the source is leveled.



sg6267d

Figure 10-9. Analog Bus Node 7

Node 8 A3 Gnd (ground)

A10 Digital IF

To observe the A10 analog bus nodes perform step A10, below. Then follow the node-specific instructions.

Step A10.

Press:

[PRESET]
[MEAS] ANALOG IN
[MARKER]
[SYSTEM] SERVICE MENU ANALOG BUS ON
[FORMAT] MORE REAL

Node 9 +0.37 V (+0.37 V reference)

Perform step A10, above, and then press [MEAS] ANALOG IN
RESOLUTION [HIGH] 9 x1.

Check for a flat line at approximately +0.37 V. This is used as the voltage reference in the “Analog Bus Correction Constants” adjustment procedure. The voltage level should be the same in high and low resolution; the absolute level is not critical.

Node 10 +2.50 V (+2.50 V reference)

Perform step A10, above, and then press [MEAS] ANALOG IN
RESOLUTION [LOW] 10 x1 SCALE REF 1 x1.

Check for a flat line at approximately +2.5 V. This voltage is used in the “Analog Bus Correction Constants” adjustment as a reference for calibrating the analog bus low resolution circuitry.

Node 11 Aux Input (rear panel input)

Perform step A10, above, and then press **MEAS** ANALOG IN **(1)** **(1)** **(x1)**.

This selects the rear panel AUX INPUT to drive the analog bus for voltage and frequency measurements. It can be used to look at test points within the instrument, using the analyzer's display as an oscilloscope. Connect the test point of interest to the rear panel AUX INPUT BNC connector.

This feature can be useful if an oscilloscope is not available. Also, it can be used for testing voltage-controlled devices by connecting the driving voltage of the device under test to the AUX IN connector. Look at the driving voltage on one display channel, while displaying the S-parameter response of the test device on the other display channel.

With **AUX OUT** switched ON, you can examine the analyzer's analog bus nodes with external equipment (see **AUX OUT** on **OFF** under the "Analog Bus Menu" heading). For HP-IB considerations, see "HP-IB Service Mnemonic Definitions," located later in this chapter.

Node 12 A10 Gnd (ground reference)

This node is used in the "Analog Bus Correction Constants" adjustment as a reference for calibrating the analog bus low and high resolution circuitry.

A11 Phase Lock

To observe the A11 analog bus nodes perform step A11, below. Then follow the node-specific instructions.

Step A11.

Press:

PRESET

MEAS ANALOG IN

MARKER

SYSTEM SERVICE MENU ANALOG BUS ON

FORMAT MORE REAL

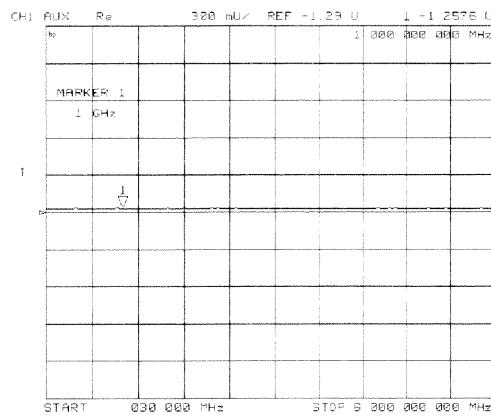
Node 13 VCO Tune 2 (not used)

10-34 Service Key Menus and Error Messages

Node 14 Vbb Ref (ECL reference voltage level)

Perform step A11, above, and then press [MEAS] ANALOG IN [14] [x1] [SCALE REF] [3] [x1] REFERENCE VALUE [-1.29] [x1].

The trace should be a flat line across the entire operation frequency range within 0.3 V (one division) of the reference value. Vbb Ref is used to compensate for ECL voltage drift.



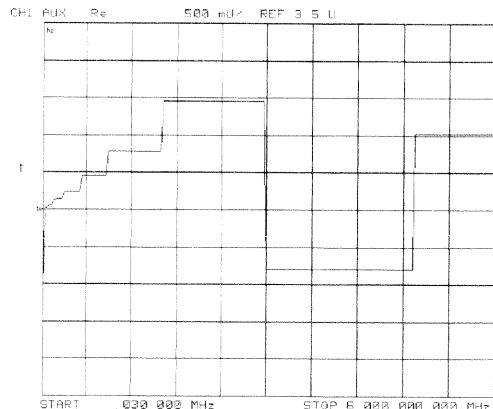
sg6268d

Figure 10-10. Analog Bus Node 14

Node 15 Pretune (open-loop source pretune voltage)

Perform step A11, above, and then press **MEAS** **ANALOG IN** **(15)** **(x1)** **SCALE REF**
AUTOSCALE.

This node displays the source pretune signal and should look like a stair-stepped ramp. Each step corresponds to the start of a band.



sg6269d

Figure 10-11. Analog Bus Node 15

Node 16 1V/GHz (source oscillator tuning voltage)

Perform step A11, above, and then press [MEAS] ANALOG IN [16] [x1] [SCALE REF]
AUTOSCALE .

This node displays the tuning voltage ramp used to tune the source oscillator. You should see a voltage ramp like the one shown in Figure 10-12. If this waveform is correct, you can be confident that the A11 phase lock assembly, the A3 source assembly, the A13/A14 fractional-N assemblies, and the A7 pulse generator are working correctly and the instrument is phase locked. If you see anything else, refer to the “Source Troubleshooting” chapter.

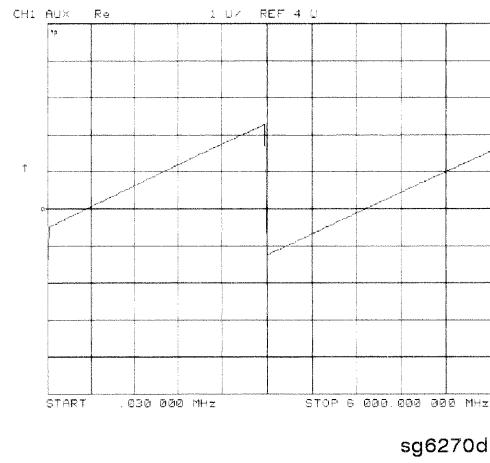


Figure 10-12. Analog Bus Node 16

Node 17 1st IF (IF used for phase lock)

Perform step A11, above, and then press [MEAS] ANALOG IN (17) (x1)
COUNTER: ANALOG BUS [MENU] CW FREQ.

Vary the frequency and compare the results to the table below.

Entered Frequency	Counter Reading
0.2 to 15.999 MHz	same as entered
16 MHz to 3 GHz	1 MHz

This node displays the IF frequency (see node17) as it enters the A11 phase lock assembly via the A4 R sampler assembly. This signal comes from the R sampler output and is used to phase lock the source.

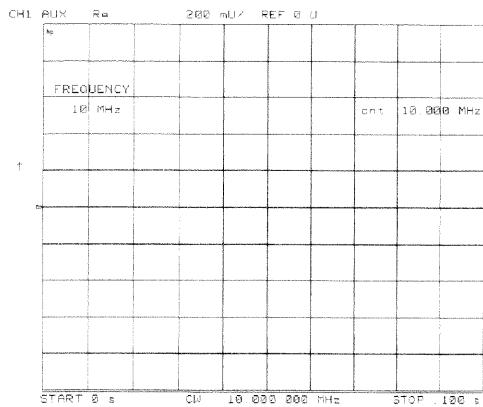
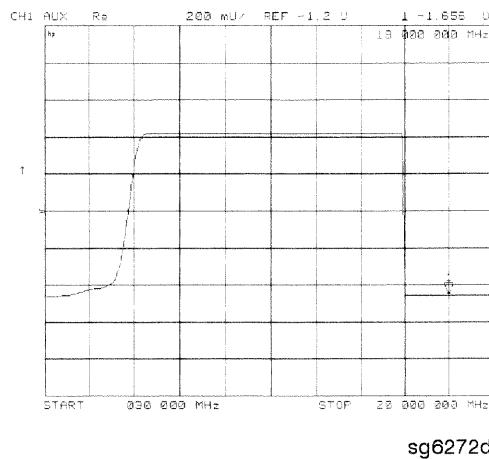


Figure 10-13. Counter Readout Location

Node 18 IF Det 2N (IF on A11 phase lock after 3 MHz filter)

Perform step A11, above, and then press [MEAS] ANALOG IN 18 x1 STOP 20 M/ μ SCALE REF AUTOSCALE.

This node detects the IF within the low pass filter/limiter. The filter is used during the track and sweep sequences but never in band 1 (3.3 to 16 MHz). The low level (about -1.7 V) means IF is in the passband of the filter. This node can be used with the FRAC N TUNE and SRC TUNE service modes.



sg6272d

Figure 10-14. Analog Bus Node 18**Node 19 IF Det 2W (IF after 16 MHz filter)**

Perform step A11, above, and then press [MEAS] ANALOG IN 19 x1 MENU STOP 20 x1 SCALE REF .2 x1 REFERENCE VALUE -1.2 x1.

This node detects IF after the 16 MHz filter/limiter. The filter is used during pretune and acquire, but not in band 1. Normal state is a flat line at about -1.7 V.

Node 20 IF Det 1 (IF after 30 MHz filter)

Perform step A11, above and then press [MEAS] ANALOG IN [20] [x1] SCALE REF [0.3] [x1] REFERENCE VALUE [-1.29] [x1].

The trace should be a flat line across the entire frequency band at least 0.5 V greater than Vbb (node 14). The correct trace indicates the presence of IF after the first 30 MHz filter/limiter.

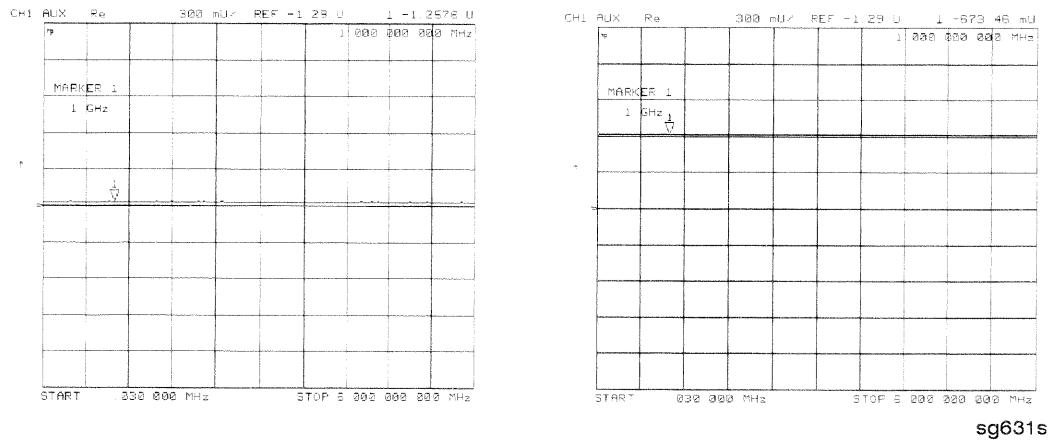


Figure 10-15. Analog Bus Node 20

A12 Reference

To observe the A12 analog bus nodes perform step A12, below. Then follow the node-specific instructions.

Step A12.

Press:

- [PRESET]
- [MEAS] ANALOG IN
- [MARKER]
- [SYSTEM] SERVICE MENU ANALOG BUS ON
- [FORMAT] MORE REAL

Node 21 100 kHz (100 kHz reference frequency)

Perform step A12, above, and then press [MEAS] ANALOG IN [21] [x1]

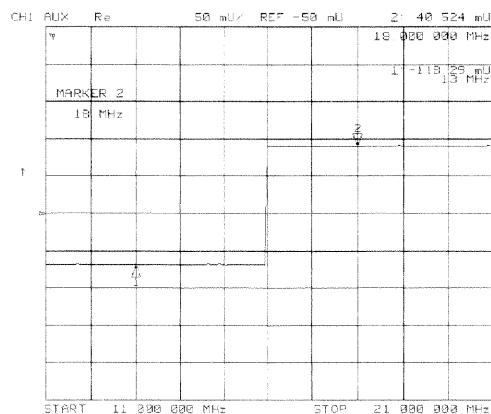
COUNTER: ANALOG BUS . This node counts the A12 100 kHz reference signal that is used on A13 (the fractional-N analog assembly) as a reference frequency for the phase detector.

Node 22 A12 Gnd 1 (ground)

Node 23 VCO Tune (A12 VCO tuning voltage)

Perform Step A12, above, and then press [START] [11] [M/ μ] [STOP] [21] [M/ μ]
[MEAS] ANALOG IN [23] [x1] [MARKER] [SCALE REF] AUTO SCALE .

The trace should show a voltage step as shown in Figure 10-16. At normal operation, the left half trace should be 0 ± 1000 mV and the right half trace should be 100 to 200 mV higher (that is, one to two divisions). If the trace does not appear as shown in Figure 10-16, refer to the “High/Low Band Transition Adjustment” in the “Adjustments and Correction Constants” chapter.



sg6273d

Figure 10-16. Analog Bus Node 23

Node 24 2nd LO

Perform step A12, above, and then press [MEAS] ANALOG IN (24) [x1]
COUNTER: ANALOG BUS [MENU] CW FREQ.

This node counts the 2nd LO used by the sampler/mixer assemblies to produce the 2nd IF of 4 kHz. As you vary the frequency, the counter reading should change to values very close to those indicated below:

Frequency Entered	Counter Reading
0.03 to 1 MHz	frequency entered - 4 kHz
1 to 16 MHz	not accurate
16 to 3,000 MHz	996 kHz

Node 25 PL Ref (phase lock reference)

Perform step A12, above, and then press [MEAS] ANALOG IN (25) [x1]
COUNTER: ANALOG BUS [MENU] CW FREQ.

This node counts the reference signal used by the phase comparator circuit on the A11 phase lock assembly. As you vary the frequency, the counter reading should change as indicated below:

Frequency Entered	Counter Reading
0.3 to 1 MHz	frequency entered
1 to 16 MHz	not accurate
16 to 3,000 MHz	1 MHz

Node 26 Ext Ref (rear panel external reference input)

Perform step A12, above, and then press [MEAS] ANALOG IN [26] [x1].

The voltage level of this node indicates whether an external reference timebase is being used:

- No external reference: about -0.9 V
- With external reference: about -0.6 V.

Node 27 VCXO Tune (40 MHz VCXO tuning voltage)

Perform step A12, above, and then press [MEAS] ANALOG IN [27] [x1]

[MARKER FCTN] MARKER →REFERENCE .

This node displays the voltage used to fine tune the A12 reference VCXO to 40 MHz. You should see a flat line at some voltage level (the actual voltage level varies from instrument to instrument). Anything other than a flat line indicates that the VCXO is tuning to different frequencies. Refer to the “Frequency Accuracy” adjustment procedure.

Node 28 A12 Gnd 2 (ground reference)**A14 Fractional-N (Digital)**

To observe the A14 analog bus nodes perform step A14, below. Then follow the node-specific instructions.

Step A14.

Press:

[PRESET]

[MEAS] ANALOG IN

[SYSTEM] SERVICE MENU ANALOG BUS ON

[FORMAT] MORE REAL

Node 29 FN VCO Tun (A14 FN VCO tuning voltage)

Perform step A14, above, and then press [MEAS] ANALOG IN [29] [x1] [SCALE REF] AUTOSCALE .

Observe the A14 FN VCO tuning voltage. If the A13 and A14 assemblies are functioning correctly and the VCO is phase locked, the trace should look like Figure 10-17. Any other waveform indicates that the FN VCO is not phase locked. The vertical lines in the trace indicate the band crossings. (The counter can also be enabled to count the VCO frequency in CW mode.)

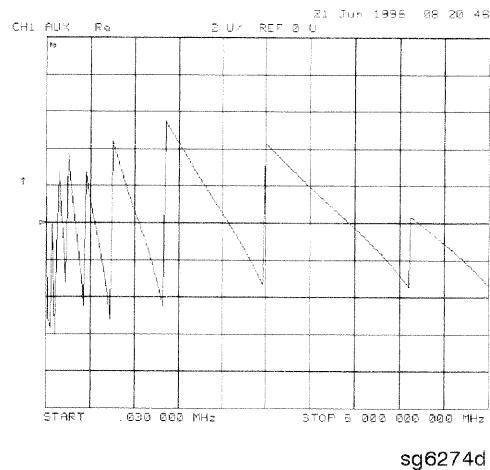
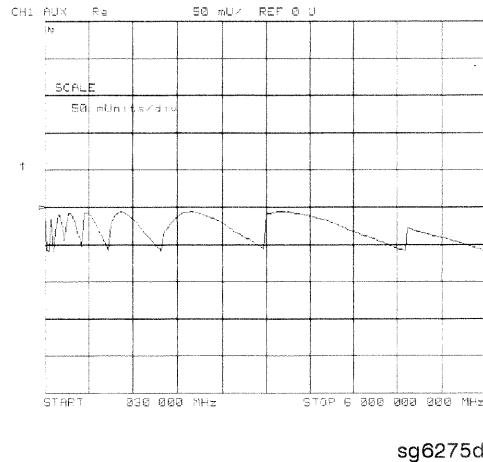


Figure 10-17. Analog Bus Node 29

Node 30 FN VCO Det (A14 VCO detector)

Perform step A14, above, and then press [MEAS] ANALOG IN [30] [x1]
RESOLUTION [HIGH] [SCALE REF] [50] [k/m].

See whether the FN VCO is oscillating. The trace should resemble Figure 10-18.



sg6275d

Figure 10-18. Analog Bus Node 30

Node 31 Count Gate (analog bus counter gate)

Perform step A14, above, and then press [MEAS] ANALOG IN [31] [x1] [SCALE REF] [2] [x1].

You should see a flat line at +5 V across the operating frequency range. The counter gate activity occurs during bandswitches, and therefore is not visible on the analog bus. To view the bandswitch activity, look at this node on an oscilloscope, using AUX OUT ON. Refer to AUX OUT on OFF under the Analog Bus Menu heading.

PEEK/POKE Menu

To access this menu, press **SYSTEM** SERVICE MENU PEEK/POKE.

PEEK/POKE Allows you to edit the content of one or more memory addresses. The keys are described below.

Caution The PEEK/POKE capability is intended for service use only.

PEEK/POKE ADDRESS (PEEL[D])	Accesses any memory address and shows it in the active entry area of the display. Use the front panel knob, entry keys, or step keys to enter the memory address of interest.
PEEK (PEEK)	Displays the data at the accessed memory address.
POKE (POKE[D])	Allows you to change the data at the memory address accessed by the PEEK/POKE ADDRESS softkey. Use the front panel knob, entry keys, or step keys to change the data. The A9CC jumper must be in the "ALTER" position in order to poke.
RESET MEMORY	Resets or clears the memory where instrument states are stored. To do this, press RESET MEMORY [PRESET] .

Firmware Revision Softkey

Press **SYSTEM** SERVICE MENU FIRMWARE REVISION to display the current firmware revision information. The number and implementation date appear in the active entry area of the display as shown in Figure 10-19 below. The analyzer's serial number and installed options are also displayed. Another way to display the firmware revision information is to cycle the line power.

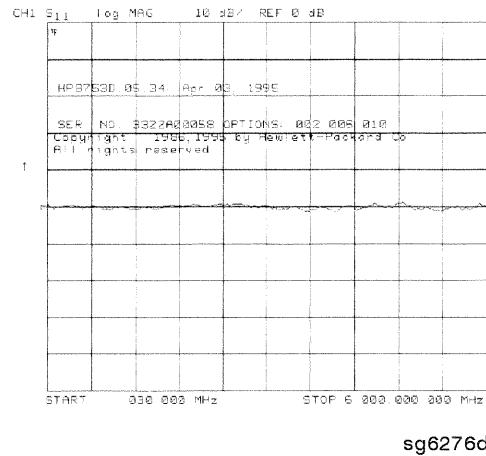


Figure 10-19. Location of Firmware Revision Information on Display

HP-IB Service Mnemonic Definitions

All service routine keystrokes can be made through HP-IB in one of the following approaches:

- sending equivalent remote HP-IB commands. (Mnemonics have been documented previously with the corresponding keystroke.)
- invoking the System Menu (MENUSYST) and using the analyzer mnemonic (SOFTn), where "n" represents the softkey number. (Softkeys are numbered 1 to 8 from top to bottom.)

An HP-IB overview is provided in the "Compatible Peripherals" chapter in the *User's Guide*. HP-IB programming information is also provided in the Programming Guide.

Invoking Tests Remotely

Many tests require a response to the displayed prompts. Since bit 1 of the Event Status Register B is set (bit 1 = service routine waiting) any time a service routine prompts the user for an expected response, you can send an appropriate response using one of the following techniques:

- Read event status register B to reset the bit.
- Enable bit 1 to interrupt (ESNB[D]). See "Status Reporting" in the *Programming Guide*.
- Respond to the prompt with a TESRn command (see Tests Menu, at the beginning of this chapter).

Symbol Conventions

[]	An optional operand
D	A numerical operand
< >	A necessary appendage
	An either/or choice in appendages

Analog Bus Codes

ANAI[D]	Measures and displays the analog input. The preset state input to the analog bus is the rear panel AUX IN. The other 30 nodes may be selected with D only if the ABUS is enabled (ANABon).
OUTPCNTR	Outputs the counter's frequency data.
OUTPERRO	Reads any prompt message sent to the error queue by a service routine.
OUTPTESS	Outputs the integer status of the test most recently executed. Status codes are those listed under "TST?".
TST?	Executes the power-on self test (internal test 1) and outputs an integer test status. Status codes are as follows: 0 = pass 1 = fail 2 = in progress 3 = not available 4 = not done 5 = done

Error Messages

This section contains an alphabetical list of the error messages that pertain to servicing the analyzer. The information in the list includes explanations of the displayed messages and suggestion to help solve the problem.

Note	The error messages that pertain to measurement applications are included in the <i>HP 8753D Network Analyzer User's Guide</i> .
-------------	---

BATTERY FAILED. STATE MEMORY CLEARED

Error Number The battery protection of the non-volatile CMOS memory has
183 failed. The CMOS memory has been cleared. Refer to the
“Assembly Replacement and Post-Repair Procedures” chapter
for battery replacement instructions. See the “Preset State and
Memory Allocation,” chapter in the *HP 8753D Network*
Analyzer User's Guide for more information about the CMOS
memory.

BATTERY LOW! STORE SAVE REGS TO DISK

Error Number The battery protection of the non-volatile CMOS memory is in
184 danger of failing. If this occurs, all of the instrument state
registers stored in CMOS memory will be lost. Save these states
to a disk and refer to the “Assembly Replacement and
Post-Repair Procedures” chapter for battery replacement
instructions. See the “Preset State and Memory Allocation,”
chapter in the *HP 8753D Network Analyzer User's Guide* for
more information about the CMOS memory.

CALIBRATION ABORTED

Error Number You have changed the active channel during a calibration so the
74 calibration in progress was terminated. Make sure the
appropriate channel is active and restart the calibration.

CALIBRATION REQUIRED

Error Number A calibration set could not be found that matched the current
63 stimulus state or measurement parameter. You will have to
perform a new calibration.

CORRECTION CONSTANTS NOT STORED

Error Number A store operation to the EEPROM was not successful. You must
3 change the position of the jumper on the A9 CPU assembly.
Refer to the "A9 CC Jumper Position Procedure" in the
"Adjustments and Correction Constants" chapter.

CORRECTION TURNED OFF

Error Number Critical parameters in your current instrument state do not
66 match the parameters for the calibration set, therefore
correction has been turned off. The critical instrument state
parameters are sweep type, start frequency, frequency span,
and number of points.

CURRENT PARAMETER NOT IN CAL SET

Error Number Correction is not valid for your selected measurement
64 parameter. Either change the measurement parameters or
perform a new calibration.

DEADLOCK

Error Number A fatal firmware error occurred before instrument preset
111 completed.

DEVICE: not on, not connect, wrong addrs

Error Number The device at the selected address cannot be accessed by the
119 analyzer. Verify that the device is switched on, and check the
HP-IB connection between the analyzer and the device. Ensure
that the device address recognized by the analyzer matches the
HP-IB address set on the device itself.

DISK HARDWARE PROBLEM

Error Number The disk drive is not responding correctly. Refer to the disk
39 drive operating manual.

DISK MESSAGE LENGTH ERROR

Error Number The analyzer and the external disk drive aren't communicating
190 properly. Check the HP-IB connection and then try substituting
another disk drive to isolate the problem instrument.

DISK: not on, not connected, wrong addrs

Error Number The disk cannot be accessed by the analyzer. Verify power to
38 the disk drive, and check the HP-IB connection between the
analyzer and the disk drive. Ensure that the disk drive address
recognized by the analyzer matches the HP-IB address set on
the disk drive itself.

DISK READ/WRITE ERROR

Error Number There may be a problem with your disk. Try a new floppy disk.
189 If a new floppy disk does not eliminate the error, suspect
 hardware problems.

INITIALIZATION FAILED

Error Number The disk initialization failed, probably because the disk is
47 damaged.

INSUFFICIENT MEMORY , PWR MTR CAL OFF

Error Number There is not enough memory space for the power meter
154 calibration array. Increase the available memory by clearing one
 or more save/recall registers, or by reducing the number of
 points.

NO CALIBRATION CURRENTLY IN PROGRESS

Error Number The RESUME CAL SEQUENCE softkey is not valid unless a
69 calibration is already in progress. Start a new calibration.

NOT ENOUGH SPACE ON DISK FOR STORE

Error Number The store operation will overflow the available disk space.
44 Insert a new disk or purge files to create free disk space.

NO FILE(S) FOUND ON DISK

Error Number No files of the type created by an analyzer store operation were
45 found on the disk. If you requested a specific file title, that file
was not found on the disk.

NO IF FOUND: CHECK R INPUT LEVEL

Error Number The first IF signal was not detected during pretune. Check the
5 front panel R channel jumper. If there is no visible problem
with the jumper, refer to the "Source Troubleshooting" chapter.

NO PHASE LOCK: CHECK R INPUT LEVEL

Error Number The first IF signal was detected at pretune, but phase lock could
7 not be acquired. Refer to the "Source Troubleshooting" chapter.

NO SPACE FOR NEW CAL. CLEAR REGISTERS

Error Number You cannot store a calibration set due to insufficient memory.
70 You can free more memory by clearing a saved instrument state
from an internal register (which may also delete an associated
calibration set, if all the instrument states using the calibration
kit have been deleted). You can store the saved instrument state
and calibration set to a disk before clearing them. After deleting
the instrument states, press **PRESET** to run the memory packer.

NOT ALLOWED DURING POWER METER CAL

Error Number When the analyzer is performing a power meter calibration, the
198 HP-IB bus is unavailable for other functions such as printing or
plotting.

OVERLOAD ON INPUT A , POWER REDUCED

Error Number See error number 57.
58

OVERLOAD ON INPUT B , POWER REDUCED

Error Number See error number 57.
59

OVERLOAD ON INPUT R , POWER REDUCED

Error Number You have exceeded approximately +14 dBm at one of the test
57 ports. The RF output power is automatically reduced to
–85 dBm. The annotation P \downarrow appears in the left margin of the
display to indicate that the power trip function has been
activated. When this occurs, reset the power to a lower level,
then toggle the SOURCE PWR on OFF softkey to switch on the
power again.

PARALLEL PORT NOT AVAILABLE FOR GPIO

Error Number You have defined the parallel port as COPY for sequencing in
165 the HP-IB menu. To access the parallel port for general purpose
I/O (GPIO), set the selection to [GPIO].

PARALLEL PORT NOT AVAILABLE FOR COPY

Error Number You have defined the parallel port as general purpose I/O (GPIO)
167 for sequencing. The definition was made under the **LOCAL** key
menus. To access the parallel port for copy, set the selection to
PARALLEL [COPY].

PHASE LOCK CAL FAILED

Error Number An internal phase lock calibration routine is automatically
4 executed at power-on, preset, and any time a loss of phase lock
is detected. This message indicates that phase lock calibration
was initiated and the first IF detected, but a problem prevented
the calibration from completing successfully. Refer to Chapter
3, "Adjustments and Correction Constants" and execute pretune
correction (test 48).

This message may appear if you connect a mixer between the
RF output and R input before turning on frequency offset mode.
Ignore it: it will go away when you turn on frequency offset.
This message may also appear if you turn on frequency offset
mode before you define the offset.

PHASE LOCK LOST

Error Number Phase lock was acquired but then lost. Refer to the "Source
8 Troubleshooting" chapter.

POSSIBLE FALSE LOCK

Error Number Phase lock has been achieved, but the source may be phase
6 locked to the wrong harmonic of the synthesizer. Perform the
source pretune correction routine documented in the
"Adjustments and Correction Constants" chapter.

POWER UNLEVELED

Error Number There is either a hardware failure in the source or you have
179 attempted to set the power level too high. Check to see if the
power level you set is within specifications. If it is, refer to the
"Source Troubleshooting" chapter. You will only receive this
message over the HP-IB. On the analyzer, P? is displayed.

POW MET INVALID

Error Number The power meter indicates an out-of-range condition. Check the
116 test setup.

POW MET NOT SETTLED

Error Number Sequential power meter readings are not consistent. Verify that
118 the equipment is set up correctly. If so, preset the instrument
and restart the operation.

POW MET: not on, not connected, wrong addrs

Error Number The power meter cannot be accessed by the analyzer. Verify
117 that the power meter address and model number set in the
analyzer match the address and model number of the actual
power meter.

POWER SUPPLY HOT!

Error Number The temperature sensors on the A8 post-regulator assembly
21 have detected an over-temperature condition. The power
supplies regulated on the post-regulator have been shut down.
Refer to the "Power Supply Troubleshooting" chapter.

POWER SUPPLY SHUT DOWN!

Error Number One or more supplies on the A8 post-regulator assembly have
22 been shut down due to an over-current, over-voltage, or
under-voltage condition. Refer to the "Power Supply
Troubleshooting" chapter.

PRINTER: error

Error Number The parallel port printer is malfunctioning. The analyzer cannot
175 complete the copy function.

PRINTER: not handshaking

Error Number The printer at the parallel port is not responding.
177

10-58 Service Key Menus and Error Messages

PRINTER: not on, not connected, wrong addrs

Error Number 24 The printer does not respond to control. Verify power to the printer, and check the HP-IB connection between the analyzer and the printer. Ensure that the printer address recognized by the analyzer matches the HP-IB address set on the printer itself.

PROBE POWER SHUT DOWN!

Error Number 23 The analyzer biasing supplies to the HP 85024A external probe are shut down due to excessive current. Troubleshoot the probe, and refer to the "Power Supply Troubleshooting" chapter.

SAVE FAILED. INSUFFICIENT MEMORY

Error Number 151 You cannot store an instrument state in an internal register due to insufficient memory. Increase the available memory by clearing one or more save/recall registers and pressing **[PRESET]**, or by storing files to a disk.

SELF TEST #n FAILED

Service Error Internal test #n has failed. Several internal test routines are
Number 112 executed at instrument preset. The analyzer reports the first failure detected. Refer to the internal tests and the self-diagnose feature descriptions earlier in this chapter.

SOURCE POWER TRIPPED , RESET UNDER POWER MENU

Information You have exceeded the maximum power level at one of the inputs and power has been automatically reduced. The annotation P↓ indicates that power trip has been activated.
Message When this occurs, reset the power and then press [MENU] POWER SOURCE PWR on OFF, to switch on the power. This message follows error numbers 57, 58, and 59.

SYSTEM IS NOT IN REMOTE

Error Number The analyzer is in local mode. In this mode, the analyzer will
52 not respond to HP-IB commands with front panel key
equivalents. It will, however, respond to commands that have
no such equivalents, such as status requests.

SWEEP MODE CHANGED TO CW TIME SWEEP

Error Number If you select external source auto or manual instrument mode
187 and you do not also select CW mode, the analyzer is
automatically switched to CW.

TEST ABORTED

Error Number You have prematurely stopped a service test.
113

TROUBLE! CHECK SETUP AND START OVER

Service Error Your equipment setup for the adjustment procedure in progress
Number 115 is not correct. Check the setup diagram and instructions in the
“Adjustments and Correction Constants” chapter. Start the
procedure again.

WRONG DISK FORMAT , INITIALIZE DISK

Error Number You have attempted to store, load, or read file titles, but your
77 disk format does not conform to the Logical Interchange Format
(LIF). You must initialize the disk before reading or writing to it.

Error Terms

The analyzer generates and stores factors in internal arrays when a measurement error-correction (measurement calibration) is performed. These factors are known by the following terms:

- error terms
- E-terms
- measurement calibration coefficients

The analyzer creates error terms by measuring well-defined calibration devices over the frequency range of interest and comparing the measured data with the ideal model for the devices. The differences represent systematic (repeatable) errors of the analyzer system. The resulting calibration coefficients are good representations of the systematic error sources. For details on the various levels of error-correction, refer to the “Optimizing Measurement Results” chapter of the *HP 8753D Network Analyzer User’s Guide*. For details on the theory of error-correction, refer to the “Application and Operation Concepts” chapter of the *HP 8753D Network Analyzer User’s Guide*.

Error Terms Can Also Serve a Diagnostic Purpose

Specific parts of the analyzer and its accessories directly contribute to the magnitude and shape of the error terms. Since we know this correlation and we know what typical error terms look like, we can examine error terms to monitor system performance (preventive maintenance) or to identify faulty components in the system (troubleshooting).

- **Preventive Maintenance:** A stable, repeatable system should generate repeatable error terms over long time intervals, for example, six months. If you make a hardcopy record (print or plot) of the error terms, you can periodically compare current error terms with the record. A sudden shift in error terms reflects a sudden shift in systematic errors, and may indicate the need for further troubleshooting. A long-term trend often reflects drift,

connector and cable wear, or gradual degradation, indicating the need for further investigation and preventive maintenance. Yet, the system may still conform to specifications. The cure is often as simple as cleaning and gaging connectors or inspecting cables.

- **Troubleshooting:** If a subtle failure or mild performance problem is suspected, the magnitude of the error terms should be compared against values generated previously with the same instrument and calibration kit. This comparison will produce the most precise view of the problem.

However, if previously generated values are not available, compare the current values to the typical values listed in Table 11-2, and shown graphically on the plots in this chapter. If the magnitude exceeds its limit, inspect the corresponding system component. If the condition causes system verification to fail, replace the component.

Consider the following while troubleshooting:

- All parts of the system, including cables and calibration devices, can contribute to systematic errors and impact the error terms.
- Connectors must be clean, gaged, and within specification for error term analysis to be meaningful.
- Avoid unnecessary bending and flexing of the cables following measurement calibration, minimizing cable instability errors.
- Use good connection techniques during the measurement calibration. The connector interface must be repeatable. Refer to the “Principles of Microwave Connector Care” section in the “Service Equipment and Analyzer Options” chapter for information on connection techniques and on cleaning and gaging connectors.
- Use error term analysis to troubleshoot minor, subtle performance problems. Refer to the “Start Troubleshooting Here” chapter if a blatant failure or gross measurement error is evident.
- It is often worthwhile to perform the procedure twice (using two distinct measurement calibrations) to establish the degree of repeatability. If the results do not seem repeatable, check all connectors and cables.

11-2 Error Terms

Full Two-Port Error-Correction Procedure

Note

This is the most accurate error-correction procedure. Since the analyzer takes both forward and reverse sweeps, this procedure takes more time than the other correction procedures.

1. Set any measurement parameters that you want for the device measurement: power, format, number of points, IF bandwidth.
2. To access the measurement correction menus, press:

CAL

3. Assuming that your calibration kit is the 7 mm default, press:

CAL KIT SELECT CAL KIT CAL KIT: 7mm RETURN RETURN

4. To select the correction type, press:

CALIBRATE MENU FULL 2-PORT REFLECTION

5. Connect a shielded open circuit to PORT 1.

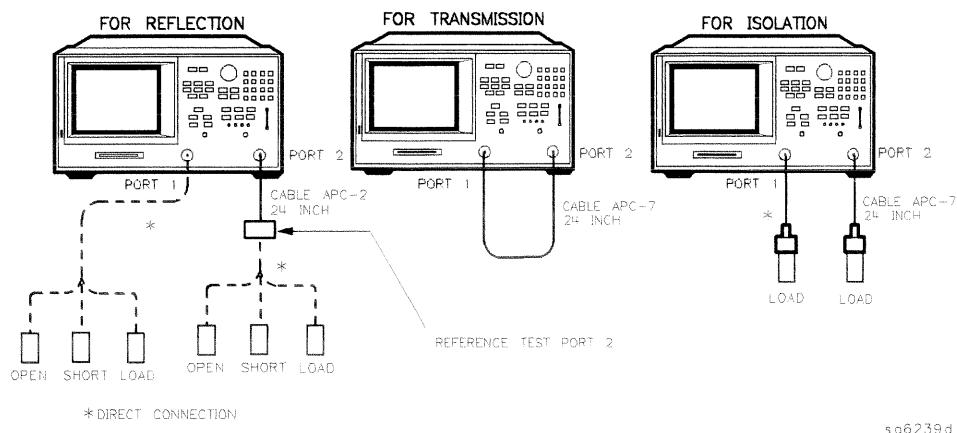


Figure 11-1. Standard Connections for Full Two-Port Error-Correction

6. To measure the standard, when the displayed trace has settled, press:

FORWARD: OPEN

The analyzer underlines the **OPEN** softkey after it measures the standard.

7. Disconnect the open, and connect a short circuit to PORT 1.

8. To measure the device, when the displayed trace has settled, press:

FORWARD: SHORT

The analyzer underlines the **SHORT** softkey after it measures the standard.

9. Disconnect the short, and connect an impedance-matched load to PORT 1.

10. To measure the standard, when the displayed trace has settled, press:

FORWARD: LOAD

The analyzer underlines the **LOAD** softkey after it measures the standard.

11. Repeat the open-short-load measurements described above, but connect the devices in turn to PORT 2, and use the **REVERSE: OPEN**, **REVERSE: SHORT**, and **REVERSE: LOAD** softkeys.

12. To compute the reflection correction coefficients, press:

STANDARDS DONE

13. To start the transmission portion of the correction, press: **TRANSMISSION**

14. Press **DO BOTH FWD + REV**

15. Press **DONE 2-PORT CAL**

16. Press **ISOLATION** and select from the following two options:

If you will be measuring devices with a dynamic range less than 90 dB, press:

OMIT ISOLATION

If you will be measuring devices with a dynamic range greater than 90 dB, follow these steps:

11-4 Error Terms

- a. Connect impedance-matched loads to PORT 1 and PORT 2.

Note

If you will be measuring highly reflective devices, such as filters, use the test device, connected to the reference plane and terminated with a load, for the isolation standard.

- b. Activate at least four times more averages than desired during the device measurement.

c. Press **CAL RESUME CAL SEQUENCE ISOLATION**

FWD ISOL'N ISOL'N STD REV ISOL'N ISOL'N STD
ISOLATION DONE .

- d. Return the averaging to the original state of the measurement, and press **CAL RESUME CAL SEQUENCE**.

17. Make a “thru” connection between PORT 1 and PORT 2, as shown in Figure 11-1.

18. To measure the standard, when the trace has settled, press:

19. Press **TRANSMISSION DO BOTH FWD + REV**

20. Press **DONE 2-PORT CAL**

The analyzer displays the corrected measurement trace. The analyzer also shows the notation **Cor** at the left of the screen, indicating that error-correction is on.

Note

You can save or store the measurement correction to use for later measurements. Use the menus under **SAVE/RECALL**, or refer to “Printing, Plotting, and Saving Measurement Results” located in the *HP 8753D Network Analyzer User’s Guide* for procedures.

21. This completes the full two-port correction procedure. You can connect and measure your device under test.

Table 11-1. Calibration Coefficient Terms and Tests

Calibration Coefficient	Calibration Type				Test Number
	Response	Response and Isolation*	1-port	2-port†	
1	E_R or E_T	$E_X (E_D)$	E_D	E_{DF}	32
2		$E_T (E_R)$	E_S	E_{SF}	33
3			E_R	E_{RF}	34
4				E_{XF}	35
5				E_{LF}	36
6				E_{TF}	37
7				E_{DR}	38
8				E_{SR}	39
9				E_{RR}	40
10				E_{XR}	41
11				E_{LR}	42
12				E_{TR}	43

NOTES:

Meaning of first subscript: D = directivity; S = source match; R = reflection tracking; X = crosstalk; L = load match; T = transmission tracking.

Meaning of second subscript: F = forward; R = reverse.

* Response and Isolation cal yields: E_X or E_T if a transmission parameter (S_{21}, S_{12}) or E_D or E_R if a reflection parameter (S_{11}, S_{22})

† One-path, 2-port cal duplicates arrays 1 to 6 in arrays 7 to 12.

11-6 Error Terms

Error Term Inspection

Note If the correction is not active, press **CAL CORRECTION ON**.

1. Press **SYSTEM SERVICE MENU TESTS** **32** **x1** **EXECUTE TEST**.

The analyzer copies the first calibration measurement trace for the selected error term into memory and then displays it. Table 11-2 lists the test numbers.

2. Press **SCALE REF** and adjust the scale and reference to study the error term trace.
3. Press **MARKER FCTN** and use the marker functions to determine the error term magnitude.
4. Compare the displayed measurement trace to the trace shown in the following "Error Term descriptions" section, and to previously measured data. If data is not available from previous measurements, refer to the typical uncorrected performance specifications listed in Table 11-2.
5. Make a hardcopy of the measurement results:
 - a. Connect a printing or plotting peripheral to the analyzer.
 - b. Press **LOCAL SYSTEM CONTROLLER SET ADDRESSES** and select the appropriate peripheral to verify that the HP-IB address is set correctly on the analyzer.
 - c. Press **COPY** and then choose either **PRINT MONOCHROME** or **PLOT**.
 - d. Press **DISPLAY MORE TITLE** and title each data trace so that you can identify it later.

for detailed information on creating hardcopies, refer to "Printing, Plotting, and Saving Measurement Results" in the *HP 8753D Network Analyzer User's Guide*.

If Error Terms Seem Worse than Typical Values

1. Perform a system verification to verify that the system still conforms to specifications.
2. If system verification fails, refer to "Start Troubleshooting Here."

Uncorrected Performance

The following table shows typical performance without error-correction. RF cables are not used except as noted. Related error terms should be within these values.

Table 11-2.
Uncorrected System Performance of HP 8753D (50Ω)
with 7 mm Test Ports

	Frequency Range			
	30 kHz to 300 kHz [*]	300 kHz to 1.3 GHz	1.3 GHz to 3 GHz	3 GHz to 6 GHz
Directivity	20 dB [†]	35 dB	30 dB	25 dB
Source Match	18 dB [‡]	16 dB	16 dB	14 dB
Load Match	20 dB [‡]	18 dB	16 dB	14 dB
Reflection Tracking	±2.0 dB	±1.5 dB	±1.5 dB	±2.5 dB
Transmission Tracking	±2.0 dB	±1.5 dB	±1.5 dB	±2.5 dB
Crosstalk	100 dB	100 dB	100 dB	90 dB

^{*} Typical
[†] 15 dB, 30 kHz to 50 kHz
[‡] 10 dB, 30 kHz to 50 kHz

11-8 Error Terms

Error Term Descriptions

The error term descriptions in this section include the following information:

- significance of each error term
- typical results following a full 2-port error-correction
- guidelines to interpret each error term

The same description applies to both the forward (F) and reverse (R) terms.

Directivity (EDF and EDR)

Description

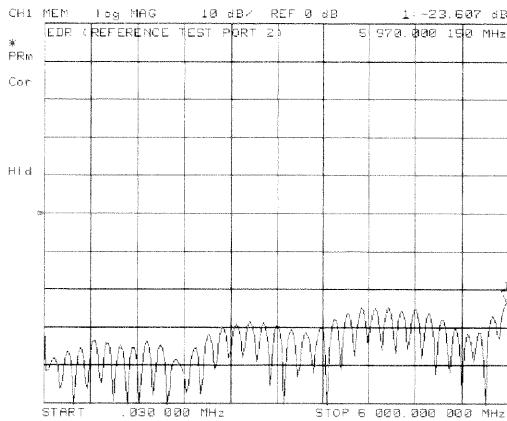
Directivity is a measure of any detected power that is reflected when a load is attached to the test port. These are the uncorrected forward and reverse directivity error terms of the system. The directivity error of the test port is determined by measuring the reflection (S_{11} , S_{22}) of the load during the error-correction procedure.

Significant System Components

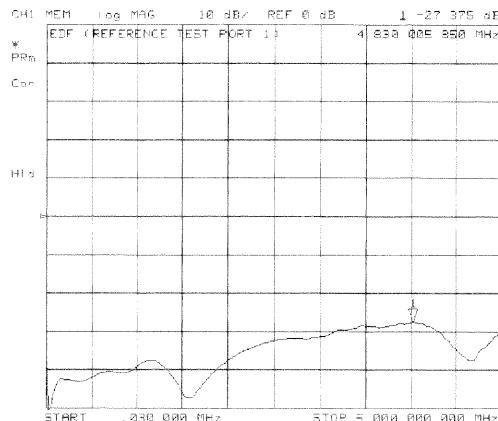
- load used in the error-correction (calibration)
- test port connectors
- test port cables

Affected Measurements

Low reflection device measurements are most affected by directivity errors.



(a)



(b)

sg632s

Figure 11-2. Typical EDF/EDR without and with Cables

11-10 Error Terms

Source Match (ESF and ESR)

Description

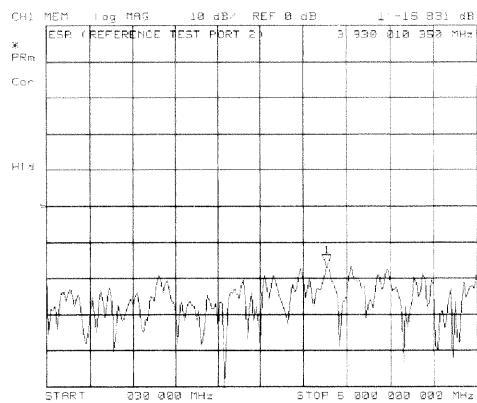
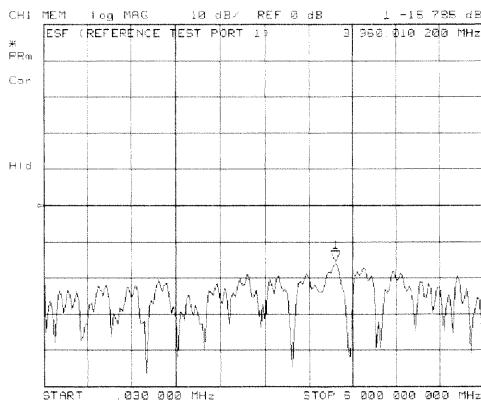
Source match is a measure of test port connector match, as well as the match between all components from the source to the test port. These are the forward and reverse uncorrected source match terms of the driven port.

Significant System Components

- load calibration kit device
- open calibration kit device
- short calibration kit device
- bridge
- test port connectors
- bias tees
- step attenuator
- transfer switch
- test port cables

Affected Measurements

Reflection and transmission measurements of highly reflective devices are most affected by source match errors.



sg633s

Figure 11-3. Typical ESF/ESR without and with Cables

Reflection Tracking (ERF and ERR)

Description

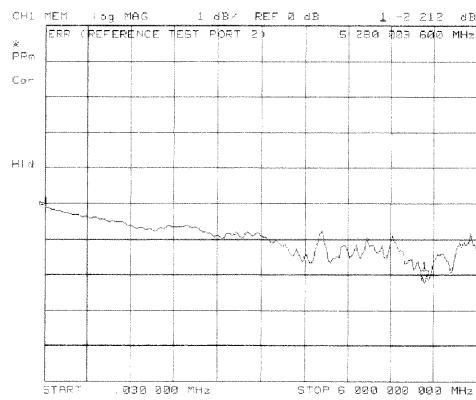
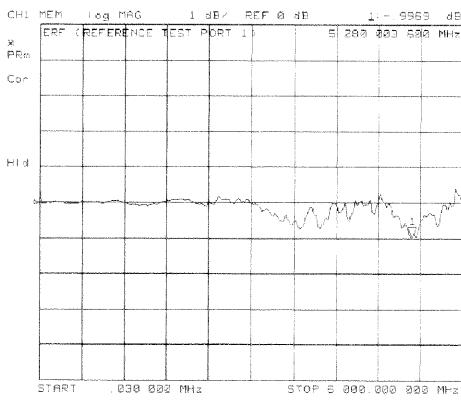
Reflection tracking is the difference between the frequency response of the reference path (R path) and the frequency response of the reflection test path (A or B input path).

Significant System Components

- open calibration kit device
- short calibration kit device
- R signal path if large variation in both ERF and ERR
- A or B input paths if only one term is affected

Affected Measurements

All reflection measurements (high or low return loss) are affected by the reflection tracking errors.



sg634s

Figure 11-4. Typical ERF/ERR without and with Cables

11-12 Error Terms

Isolation (Crosstalk, EXF and EXR)

Description

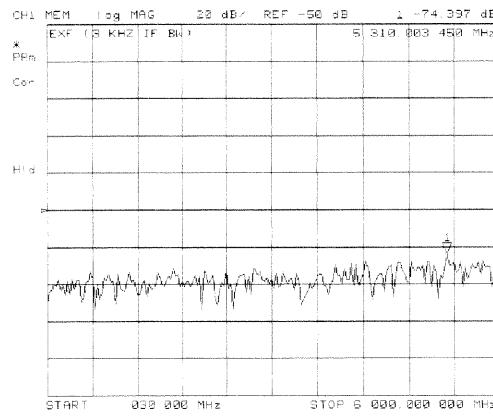
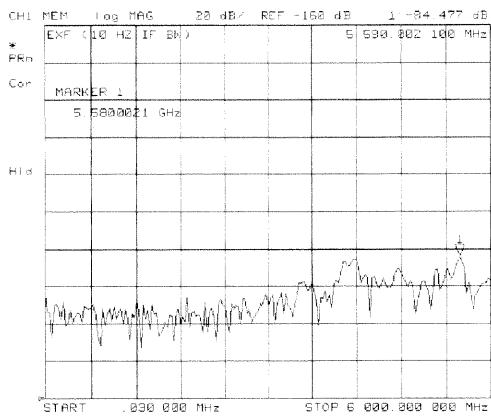
Isolation is a measure of the leakage between the test ports and the signal paths. The isolation error terms are characterized by measuring transmission (S_{21} , S_{12}) with loads attached to both ports during the error-correction procedure. Since these terms are low in magnitude, they are usually noisy (not very repeatable). The error term magnitude changes dramatically with IF bandwidth: a 10 Hz IF bandwidth must be used in order to lower the noise floor beyond the crosstalk specification. Using averaging will also reduce the peak-to-peak noise in this error term.

Significant System Components

- sampler crosstalk

Affected Measurements

Transmission measurements, (primarily where the measured signal level is very low), are affected by isolation errors. For example, transmission measurements where the insertion loss of the device under test is large.



sg638s

Figure 11-5.
Typical EXF/EXR with 10 Hz Bandwidth and with 3 kHz Bandwidth

Load Match (ELF and ELR)

Description

Load match is a measure of the impedance match of the test port that terminates the output of a 2-port device. Load match error terms are characterized by measuring the reflection (S_{11} , S_{22}) responses of a “thru” configuration during the calibration procedure.

Significant System Components

- “thru” cable
- cable connectors
- test port connectors

Affected Measurements

All transmission and reflection measurements of a low insertion loss two-port devices are most affected by load match errors. Transmission measurements of lossy devices are also affected.

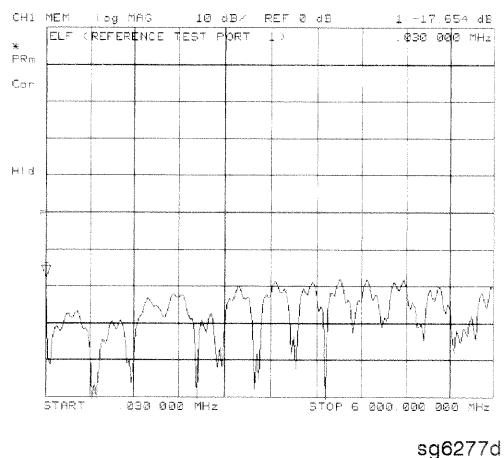


Figure 11-6. Typical ELF/ELR

Transmission Tracking (ETF and ETR)

Description

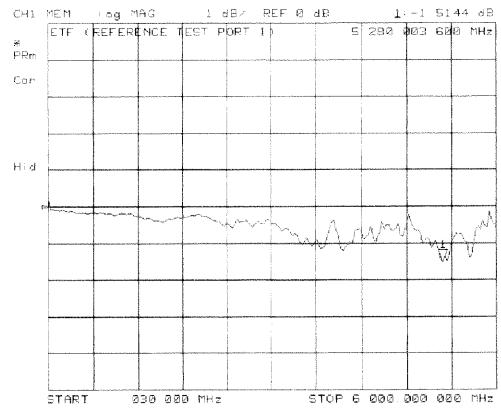
Transmission tracking is the difference between the frequency response of the reference path (including R input) and the transmission test path (including A or B input) while measuring transmission. The response of the test port cables is included. These terms are characterized by measuring the transmission (S21, S12) of the "thru" configuration during the error-correction procedure.

Significant System Components

- R signal path (if both ETF and ETR and bad)
- A or B input paths
- "thru" cable

Affected Measurements

All transmission measurements are affected by transmission tracking errors.



sg6278d

Figure 11-7. Typical ETF/ETR

12

Theory of Operation

This chapter is divided into two major sections:

- “How the HP 8753D Works” gives a general description of the HP 8753D network analyzer operation.
- “A Close Look at the Analyzer’s Functional Groups” provides more detailed operating theory for each of the analyzer’s functional groups.

How the HP 8753D Works

Network analyzers measure the reflection and transmission characteristics of devices and networks. A network analyzer test system consists of the following:

- source
- signal-separation devices
- receiver
- display

The analyzer applies a signal that is either transmitted through the device under test, or reflected from its input, and then compares it with the incident signal generated by the swept RF source. The signals are then applied to a receiver for measurement, signal processing, and display.

The HP 8753D vector network analyzer integrates a high resolution synthesized RF source, test set, and a dual channel three-input receiver to measure and display magnitude, phase, and group delay of transmitted and reflected power. The HP 8753D Option 010 has the additional capability of transforming measured data from the frequency domain to the time domain. Figure 12-1 is a simplified block diagram of the network analyzer system. A detailed block diagram of the analyzer is located at the end of Chapter 4, “Start Troubleshooting Here.”

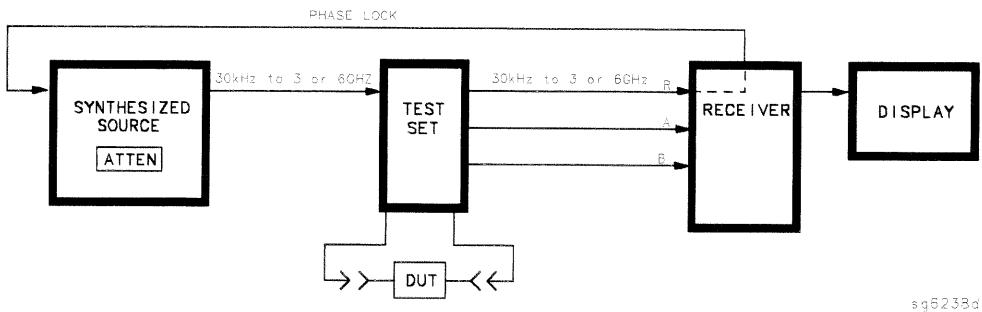


Figure 12-1. Simplified Block Diagram of the Network Analyzer System

The Built-In Synthesized Source

The analyzer's built-in synthesized source produces a swept RF signal in the range of 30 kHz to 3.0 GHz. The HP 8753D Option 006 is able to generate signals up to 6.0 GHz. The source output power is leveled by an internal ALC (automatic leveling control) circuit. To achieve frequency accuracy and phase measuring capability, the analyzer is phase locked to a highly stable crystal oscillator.

For this purpose, a portion of the transmitted signal is routed to the R channel input of the receiver, where it is sampled by the phase detection loop and fed back to the source.

The Source Step Attenuator

The 70 dB, electro-mechanical, step attenuator contained in the source has very low loss. It is used to adjust the power level to the device under test without changing the level of the incident power in the reference path. The user sets the attenuation levels via the front panel softkeys.

12-2 Theory of Operation

The Built-In Test Set

The HP 8753D features a built-in test set that provides the signal separation capability for the device under test, as well as to the signal-separation devices. The signal separation devices are needed to separate the incident signal from the transmitted and reflected signals. The incident signal is applied to the R channel input via an external jumper cable on the front panel. Meanwhile, the transmitted and reflected signals are internally routed from the test port couplers to the inputs of the A and B sampler/mixers in the receiver. Port 1 is connected to the A input and port 2 is connected to the B input.

The test set contains the hardware required to make simultaneous transmission and reflection measurements in both the forward and reverse directions. A solid-state transfer switch in the built-in test set allows reverse measurements to be made without changing the connections to the device under test.

The Receiver Block

The receiver block contains three sampler/mixers for the R, A and B inputs. The signals are sampled, and down-converted to produce a 4 kHz IF (intermediate frequency). A multiplexer sequentially directs each of the three IF signals to the ADC (analog to digital converter) where it is converted from an analog to a digital signal to be measured and processed for viewing on the display. Both amplitude and phase information are measured simultaneously, regardless of what is displayed on the analyzer.

The Microprocessor

A microprocessor takes the raw data and performs all the required error correction, trace math, formatting, scaling, averaging, and marker operations, according to the instructions from the front panel or over HP-IB. The formatted data is then displayed.

Required Peripheral Equipment

In addition to the analyzer, a system requires calibration standards for vector accuracy enhancement, and cables for interconnections.

A Close Look at the Analyzer's Functional Groups

The operation of the analyzer is most logically described in five functional groups. Each group consists of several major assemblies, and performs a distinct function in the instrument. Some assemblies are related to more than one group, and in fact all the groups are to some extent interrelated and affect each other's performance.

Power Supply. The power supply functional group consists of the A8 post regulator and the A15 preregulator. It supplies power to the other assemblies in the instrument.

Digital Control. The digital control group consists of the A1 front panel and A2 front panel processor, the A9 CPU, the A16 rear panel, the A18 display and the A19 graphics system processor (GSP). The A10 digital IF assembly is also related to this group. These assemblies combine to provide digital control for the analyzer.

Source. The source group consists of the A3 source, A7 pulse generator, A11 phase lock, A12 reference, A13 fractional-N (analog), and A14 fractional-N (digital) assemblies. The A4 sampler is also related since it is part of the source phase lock loop. The source supplies a phase-locked RF signal to the device under test.

Signal Separation. The signal separation group performs the function of an S-parameter test set, dividing the source signal into a reference path and a test path, and providing connections to the device under test. It consists of the A24 transfer switch, the A21 test port 1 coupler, and the A22 test port 2 coupler.

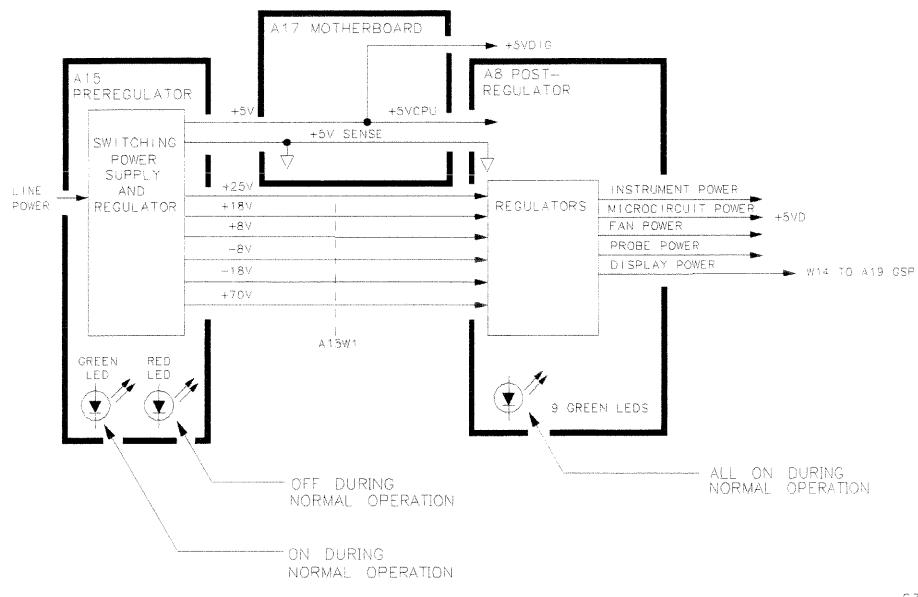
Receiver. The receiver group consists of the A4/A5/A6 sampler/mixers and the A10 digital IF. The A12 reference assembly and the A9 CPU are also related. The receiver measures and processes input signals for display.

The following pages describe the operation of each of the functional groups.

Power Supply Theory

The power supply functional group consists of the A15 preregulator and the A8 post regulator. These two assemblies comprise a switching power supply that provides regulated DC voltages to power all assemblies in the analyzer. The A15 preregulator is enclosed in a casting at the rear of the instrument behind the display. It is connected to the A8 post regulator by a wire bus A15W1.

Figure 12-2 is a simplified block diagram of the power supply group.



sg636d

Figure 12-2. Power Supply Functional Group, Simplified Block Diagram

A15 Preregulator

The A15 preregulator steps down and rectifies the line voltage. It provides a fully regulated +5 V digital supply, and several preregulated voltages that go to the A8 post regulator assembly for additional regulation.

The A15 preregulator assembly includes the line power module, a 60 kHz switching preregulator, and overvoltage protection for the +5 V digital supply. It provides LEDs, visible from the rear of the instrument, to indicate either normal or shutdown status.

Line Power Module

The line power module includes the line power switch, voltage selector switch, and main fuse. The line power switch is activated from the front panel. The voltage selector switch, accessible at the rear panel, adapts the analyzer to local line voltages of approximately 115 V or 230 V (with 350 VA maximum). The main fuse, which protects the input side of the preregulator against drawing too much line current, is also accessible at the rear panel. Refer to the *HP 8753D Network Analyzer Installation and Quick Start Guide* for line voltage tolerances and other power considerations.

Preregulated Voltages

The switching preregulator converts the line voltage to several DC voltages. The regulated +5 V digital supply goes directly to the motherboard. The following partially regulated voltages are routed through A15W1 to the A8 post regulator for final regulation:

+70 V +25 V +18 V -18 V +8 V -8 V

Regulated +5 V Digital Supply

The +5 VD supply is regulated by the control circuitry in the A15 preregulator. It goes directly to the motherboard, and from there to all assemblies requiring a low noise digital supply. A +5 V sense line returns from the motherboard to the A15 preregulator. The +5 V CPU is derived from the +5 VD in the A8 post regulator and goes directly to the A19 graphics system processor.

In order for the preregulator to function, the +5 V digital supply must be loaded by one or more assemblies, and the +5 V sense line must be working. If not, the other preregulated voltages will not be correct.

Shutdown Indications: the Green LED and Red LED

The green LED is on in normal operation. It is off when line power is not connected, not switched on, or set too low, or if the line fuse has blown.

The red LED, which is off in normal operation, lights to indicate a fault in the +5 V supply. This may be an over/under line voltage, over line current, or overtemperature condition. Refer to the troubleshooting chapters for more information.

A8 Post Regulator

The A8 post regulator filters and regulates the DC voltages received from the A15 preregulator. It provides fusing and shutdown circuitry for individual voltage supplies. It distributes regulated constant voltages to individual assemblies throughout the instrument. It includes the overtemperature shutdown circuit, the variable fan speed circuit, and the air flow detector. Nine green LEDs provide status indications for the individual voltage supplies.

Refer to the Power Supply Block Diagram located at the end of Chapter 5, "Power Supply Troubleshooting," to see the voltages provided by the A8 post regulator.

Voltage Indications: the Green LEDs

The nine green LEDs along the top edge of the A8 assembly are on in normal operation, to indicate the correct voltage is present in each supply. If they are off or flashing, a problem is indicated. The troubleshooting procedures later in this chapter detail the steps to trace the cause of the problem.

Shutdown Circuit

The shutdown circuit is triggered by overcurrent, overvoltage, undervoltage, or overtemperature. It protects the instrument by causing the regulated voltage supplies to be shut down. It also sends status messages to the A9 CPU to trigger warning messages on the analyzer display. The voltages that are not shut down are the +5VD and +5VCPU digital supplies from the preregulator, the fan supplies, the probe power supplies, and the display supplies. The shutdown circuit can be disabled momentarily for troubleshooting purposes by using a jumper to connect the SDIS line (A8TP4) to ground.

Variable Fan Circuit and Air Flow Detector

The fan power is derived directly from the +18 V and -18 V supplies from the A15 preregulator. The fan is not fused, so that it will continue to provide airflow and cooling when the instrument is otherwise disabled. If overheating occurs, the main instrument supplies are shut down and the fan runs at full speed. An overtemperature status message is sent to the A9 CPU to initiate a warning message on the analyzer display. The fan also runs at full speed if the air flow detector senses a low output of air from the fan. (Full speed is normal at initial power on.)

Display Power

The A8 assembly supplies voltages to the display through a wire cable. The A8 supplies +5VCPU and +65 V to the A19 GSP, then the +65 V is routed to the display. They are not connected to the protective shutdown circuitry so that the A18 display assemblies can operate during troubleshooting when other supplies do not work.

Probe Power

The +18 V and -18 V supplies are post regulated to +15 V and -12.6 V to provide a power source at the front panel for an external RF probe or millimeter modules.

Digital Control Theory

The digital control functional group consists of the following assemblies:

- A1 front panel
- A2 front panel processor
- A9 CPU
- A10 digital IF
- A16 rear panel
- A18 display
- A19 GSP

These assemblies combine to provide digital control for the entire analyzer. They provide math processing functions, as well as communications between the analyzer and an external controller and/or peripherals. Figure 12-3 is a simplified block diagram of the digital control functional group.

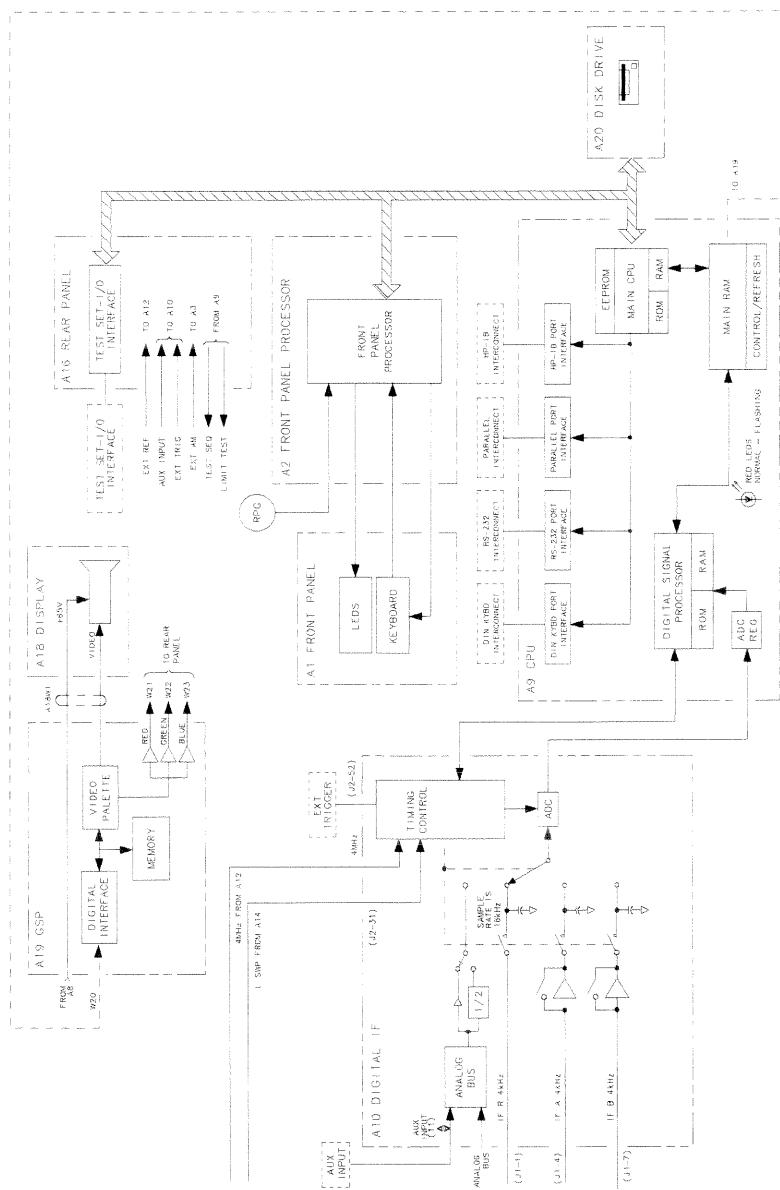


Figure 12-3. Digital Control Group, Simplified Block Diagram

Theory of Operation 12-9

A1 Front Panel

The A1 front panel assembly provides user interface with the analyzer. It includes the keyboard for local user inputs, and the front panel LEDs that indicate instrument status. The RPG (rotary pulse generator) is not electrically connected to the front panel, but provides user inputs directly to the front panel processor.

A2 Front Panel Processor

The A2 front panel processor detects and decodes user inputs from the front panel and the RPG, and transmits them to the CPU. It has the capability to interrupt the CPU to provide information updates. It controls the front panel LEDs that provide status information to the user.

A9 CPU/A10 Digital IF

The A9 CPU assembly contains the main CPU (central processing unit), the digital signal processor, memory storage, and interconnect port interfaces. The main CPU is the master controller for the analyzer, including the other dedicated microprocessors. The memory includes EEPROM, RAM, EPROM, and ROM.

Data from the receiver is serially clocked into the A9 CPU assembly from the A10 digital IF. The data taking sequence is triggered either from the A14 fractional-N assembly, externally from the rear panel, or by software on the A9 assembly.

Main CPU

The main CPU is a 16-bit microprocessor that maintains digital control over the entire instrument through the instrument bus. The main CPU receives external control information from the front panel or HP-IB, and performs processing and formatting operations on the raw data in the main RAM. It controls the digital signal processor, the front panel processor, the display processor, and the interconnect port interfaces. In addition, when the analyzer is in the system controller mode, the main CPU controls peripheral devices through the peripheral port interfaces.

The main CPU has a dedicated EPROM that contains the operating system for instrument control. Front panel settings are stored in CMOS RAM, with a battery providing at least 5 years of backup storage when external power is off.

12-10 Theory of Operation

Main RAM

The main RAM (random access memory) is shared memory for the CPU and the digital signal processor. It stores the raw data received from the digital signal processor, while additional calculations are performed on it by the CPU. The CPU reads the resulting formatted data from the main RAM and converts it to GSP commands. It writes these commands to the GSP for output to the analyzer display.

EEPROM

EEPROM (electrically-erasable programmable read only memory) contains factory set correction constants unique to each instrument. These constants correct for hardware variations to maintain the highest measurement accuracy. The correction constants can be updated by executing the routines in Chapter 3, "Adjustments and Correction Constants."

Digital Signal Processor

The digital signal processor receives the digitized data from the A10 digital IF. It computes discrete Fourier transforms to extract the complex phase and magnitude data from the 4 kHz IF signal. The resulting raw data is written into the main RAM.

A18 Display

The A18 display is a 7.5 inch raster scan CRT with associated drive circuitry. It receives a +65 V power supply from the A19 GSP, along with digital TTL horizontal and vertical sync signals, and red, green, and blue (RGB) video signals. Automatic degaussing is performed whenever the instrument is switched on to minimize the magnetization of the CRT.

A19 GSP

The A19 graphics system processor provides an interface between the A9 CPU and the A18 display. The CPU (A9) converts the formatted data to GSP commands and writes it to the GSP. The GSP processes the data to obtain the necessary video signals and sends the signals to the A18 display. It also produces RGB output signals which are sent to the A16 rear panel. The assembly receives two power supply voltages: +5VCPU, which is used for processing, and +65 V, which is passed on to A18 but not used on A19.

A16 Rear Panel

The A16 rear panel includes the following interfaces:

TEST SET I/O INTERCONNECT. This provides control signals and power to operate duplexer test adapters.

EXT REF. This allows for a frequency reference signal input that can phase lock the analyzer to an external frequency standard for increased frequency accuracy.

The analyzer automatically enables the external frequency reference feature when a signal is connected to this input. When the signal is removed, the analyzer automatically switches back to its internal frequency reference.

10 MHZ PRECISION REFERENCE. (Option 1D5) This output is connected to the EXT REF (described above) to improve the frequency accuracy of the analyzer.

AUX INPUT. This allows for a dc or ac voltage input from an external signal source, such as a detector or function generator, which you can then measure, using the S-parameter menu. (You can also use this connector as an analog output in service routines.)

EXT AM. This allows for an external analog signal input that is applied to the ALC circuitry of the analyzer's source. This input analog signal amplitude modulates the RF output signal.

EXT TRIG. This allows connection of an external negative TTL-compatible signal that will trigger a measurement sweep. The trigger can be set to external through softkey functions.

TEST SEQ. This outputs a TTL signal that can be programmed in a test sequence to be high or low, or pulse (10 μ seconds) high or low at the end of a sweep for a robotic part handler interface.

LIMIT TEST. This outputs a TTL signal of the limit test results as follows:

Pass: TTL high

Fail: TTL low

Source Theory Overview

The source produces a highly stable and accurate RF output signal by phase locking a YIG oscillator to a harmonic of the synthesized VCO (voltage controlled oscillator). The source output produces a CW or swept signal between 30 kHz and 3 GHz (or 30 kHz and 6 GHz for Option 006) with a maximum leveled power of +10 dBm. The source's built-in 70 dB step attenuator allows the power to go as low as -85 dBm.

The full frequency range of the source is produced in 14 subsweeps, one in super low band, two in low band and eleven in high band. The high band frequencies (16 MHz to 3 GHz) or (16 MHz to 6 GHz for Option 006) are achieved by harmonic mixing, with a different harmonic number for each subsweep. The low band frequencies (300 kHz to 16 MHz) are down-converted by fundamental mixing. The super low band frequencies (10 kHz to 300 kHz) are sent directly from the A12 reference board to the output of the A3 source assembly. This band is not phased locked nor does it use the ALC. It is the basic amplified output of the fractional-N synthesizer.

The source functional group consists of the individual assemblies described below.

A14/A13 Fractional-N

These two assemblies comprise the synthesizer. The 30 to 60 MHz VCO in the A14 assembly generates the stable LO frequencies for fundamental and harmonic mixing.

A12 Reference

This assembly provides stable reference frequencies to the rest of the instrument by dividing down the output of a 40 MHz crystal oscillator. In low band operation, the output of the fractional-N synthesizer is mixed down in the A12 reference assembly. (The 2nd LO signal from the A12 assembly is explained in Receiver Theory.) The A12 is also the origin of the super low band portion of the 8753D source.

A7 Pulse Generator

A step recovery diode in the pulse generator produces a comb of harmonic multiples of the VCO output. These harmonics provide the high band LO (local oscillator) input to the samplers. In low band and super low band the operation of the pulse generator is turned off.

A11 Phase Lock

This assembly compares the first IF (derived from the source output in the A4 sampler) to a stable reference, and generates an error voltage that is integrated into the drive for the A3 source assembly.

A3 Source

This assembly includes a 3.0 to 6.8 GHz YIG oscillator and a 3.8 GHz cavity oscillator. The outputs of these oscillators are mixed to produce the RF output signal. In Option 006 (30 kHz to 6 GHz) the frequencies 3.0 to 6.0 GHz are no longer a mixed product, but are the direct output of the YIG Oscillator. The signal tracks the stable output of the synthesizer. The ALC (automatic leveling control) circuitry is also in the A3 assembly.

Source Super Low Band Operation

The Super Low Band Frequency Range is 10 kHz to 300 kHz. These frequencies are generated by the A12 Reference Board. They are the amplified output of the fractional-N synthesizer. This output is not phase locked and is not subject to ALC control. Refer to Table 12-1.

Table 12-1. Super Low Band Subsweep Frequencies

Fractional-N (MHz)	1st IF (MHz)	RF Output (MHz)
40.0 to 43.3	0.010 to 0.300	0.010 to 0.300

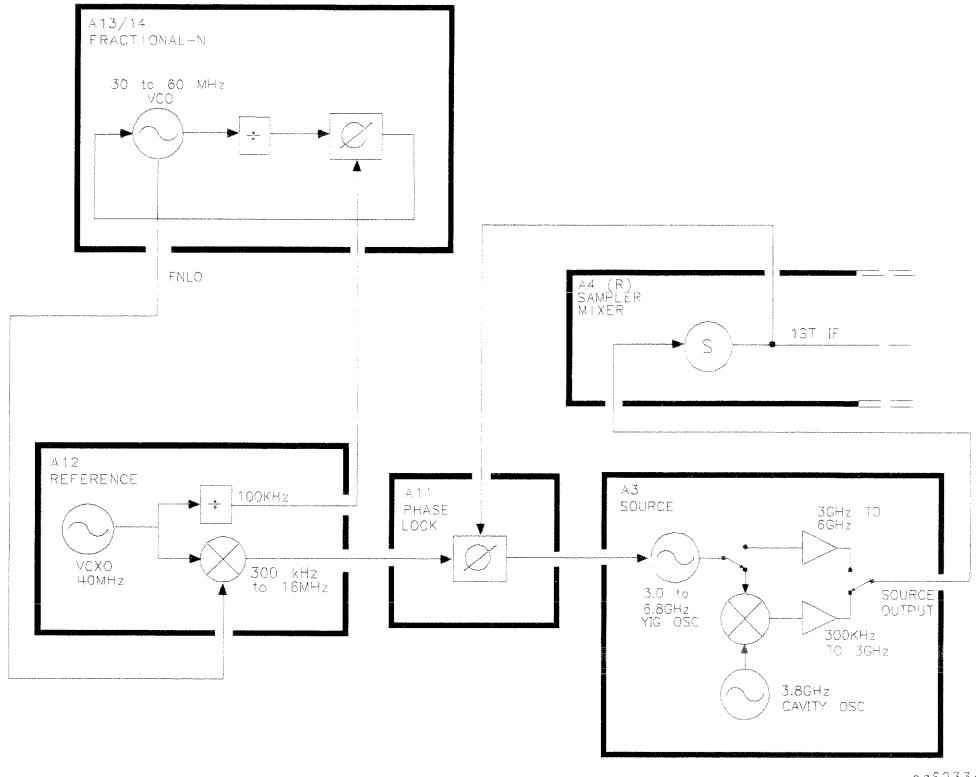
Source Low Band Operation

The low band frequency range is 300 kHz to 16 MHz. These frequencies are generated by locking the A3 source to a reference signal. The reference signal is synthesized by mixing down the fundamental output of the fractional-N VCO with a 40 MHz crystal reference signal. Low band operation differs from high band in these respects: The reference frequency for the A11 phase lock is not a fixed 1 MHz signal, but varies with the frequency of the fractional-N VCO signal. The sampler diodes are biased on to pass the signal through to the mixer. The 1st IF signal from the A4 sampler is not fixed but is identical to the source output signal and sweeps with it. The following steps outline the low band sweep sequence, illustrated in Figure 12-4.

1. **A signal (FN LO) is generated by the fractional-N VCO.** The VCO in the A14 Fractional-N assembly generates a CW or swept signal that is 40 MHz greater than the start frequency. The signal is divided down to 100 kHz and phase locked in the A13 assembly, as in high band operation.
2. **The fractional-N VCO signal is mixed with 40 MHz to produce a reference signal.** The signal (FN LO) from the Fractional-N VCO goes to the A12 reference assembly, where it is mixed with the 40 MHz VCXO (voltage controlled crystal oscillator). The resulting signal is the reference to the phase comparator in the A11 assembly.
3. **The A3 source is pretuned. The source output is fed to the A4 sampler.** The pretuned DAC in the A11 phase lock assembly sets the A3 source to a frequency 1 to 6 MHz above the start frequency. This signal (source output) goes to the A4 R input sampler/mixer assembly.
4. **The signal from the source is fed back (1st IF) to the phase comparator.** The source output signal passes directly through the sampler in the A4 assembly, because the sampler is biased on. The signal (1st IF) is fed back unaltered to the phase comparator in the A11 phase lock assembly. The other input to the phase comparator is the heterodyned reference signal from the A12 assembly. Any frequency difference between these two signals produces a proportional error voltage.
5. **A tuning signal (YO DRIVE) tunes the source and phase lock is achieved.** The error voltage is used to drive the A3 source YIG oscillator to bring the YIG closer to the reference frequency. The loop process continues until the source frequency and the reference frequency are the same, and phase lock is achieved.

6. A synthesized sub sweep is generated. The source tracks the synthesizer.

When lock is achieved at the start frequency, the synthesizer starts to sweep. This changes the phase lock reference frequency, and causes the source to track at a difference frequency 40 MHz below the synthesizer.



sg6233d

Figure 12-4. Low Band Operation of the Source

12-16 Theory of Operation

The full low band is produced in two sub sweeps, to allow addition IF filtering below 3 MHz. At the transition between subsweeps, the source is pretuned and then relocks. Table 12-2 lists the low band subsweep frequencies at the fractional-N VCO and the RF output.

Table 12-2. Low Band Subsweep Frequencies

Fractional-N (MHz)	1st IF (MHz)	Source Output (MHz)
40.3 to 43.3	0.3 to 3.3	0.3 to 3.3
43.3 to 56.0	3.3 to 16.0	3.3 to 16.0

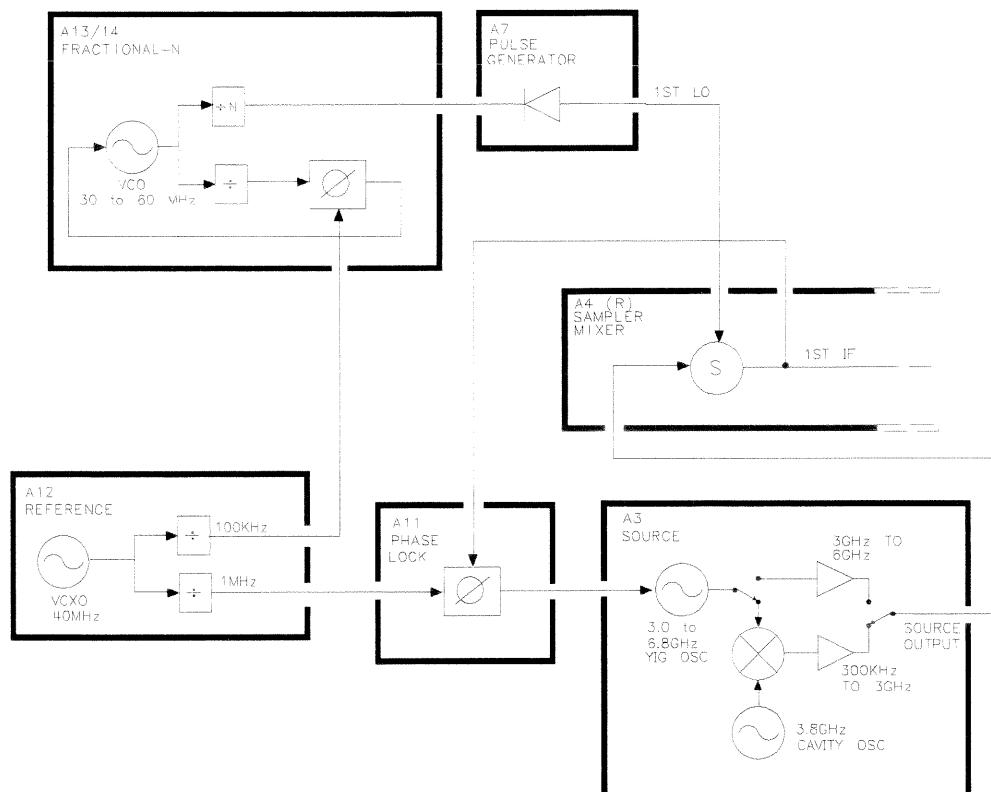
Source High Band Operation

The high band frequency range is 16 MHz to 3.0 GHz or 16 MHz to 6.0 GHz with Option 006. These frequencies are generated in subsweeps by phase-locking the A3 source signal to harmonic multiples of the fractional-N VCO. The high band subsweep sequence, illustrated in Figure 12-5, follows these steps:

1. **A signal (HI OUT) is generated by the fractional-N VCO.** The VCO in the A14 fractional-N assembly generates a CW or swept signal in the range of 30 to 60 MHz. This signal is synthesized and phase locked to a 100 kHz reference signal from the A12 reference assembly. The signal from the fractional-N VCO is divided by 1 or 2, and goes to the pulse generator.
2. **A comb of harmonics (1st LO) is produced in the A7 pulse generator.** The divided down signal from the fractional-N VCO drives a step recovery diode (SRD) in the A7 pulse generator assembly. The SRD multiplies the fundamental signal from the fractional-N into a comb of harmonic frequencies. The harmonics are used as the 1st LO (local oscillator) signal to the samplers. One of the harmonic signals is 1 MHz below the start signal set from the front panel.
3. **The A3 source is pretuned. The source output is fed to the A4 sampler.** The pretune DAC in the A11 phase lock assembly sets the A3 source to a first approximation frequency (1 to 6 MHz higher than the start frequency). This signal (RF OUT) goes to the A4 R input sampler/mixer assembly.
4. **The synthesizer signal and the source signal are combined by the sampler. A difference frequency is generated.** In the A4 sampler, the 1st LO signal from the pulse generator is combined with the source output signal. The IF (intermediate frequency) produced is a first approximation of 1 MHz. This signal (1st IF) is routed back to the A11 phase lock assembly.
5. **The difference frequency (1st IF) from the A4 sampler is compared to a reference.** The 1st IF feedback signal from the A4 is filtered and applied to a phase comparator circuit in the A11 phase lock assembly. The other input to the phase comparator is a crystal controlled 1 MHz signal from the A12 reference assembly. Any frequency difference between these two signals produces a proportional error voltage.
6. **A tuning signal (YO DRIVE) tunes the source and phase lock is achieved.** The error voltage is used to drive the A3 source YIG oscillator, in order to bring it closer to the required frequency. The loop process continues until the 1st IF feedback signal to the phase comparator is equal to the 1 MHz reference signal, and phase lock is achieved.

- 7. A synthesized subsweep is generated by A13/A14. The A3 source tracks the synthesizer.** When the source is phase locked to the synthesizer at the start frequency, the synthesizer starts to sweep. The phase locked loop forces the source to track the synthesizer, maintaining a constant 1 MHz 1st IF signal.

The full high band sweep is generated in a series of subsweeps, by phase locking the A3 source signal to harmonic multiples of the fractional-N VCO. The 16 to 31 MHz subsweep is produced by a one half harmonic, using the divide-by-2 circuit on the A14 assembly. At the transitions between subsweeps, the source is pretuned and then relocks. Table 12-3 lists the high band subsweep frequencies from the fractional-N VCO and the source output.



sg6231d

Figure 12-5. High Band Operation of the Source

Table 12-3. High Band Subsweep Frequencies

Fractional-N (MHz)	Harmonic	Source Output (MHz)
30 to 60	1/2	16 to 31
30 to 60	1	31 to 61
30 to 60	2	61 to 121
40 to 59	3	121 to 178
35.4 to 59.2	5	178 to 296
32.8 to 59.4	9	296 to 536
35.7 to 59.5	15	536 to 893
33.0 to 59.5	27	893 to 1607
31.5 to 58.8	51	1607 to 3000
Option 006		
37.0 to 59.6	83	3000 to 4950
49.0 to 59.4	101	4950 to 6000

12-20 Theory of Operation

Source Operation in other Modes/Features

Besides the normal network analyzer mode, the HP 8753D has extra modes and features to make additional types of measurements. The following describes the key differences in how the analyzer operates to achieve these new measurements.

Frequency Offset

The analyzer can measure frequency-translating devices with the frequency offset feature.

The receiver operates normally. However, the source is pretuned to a different frequency by an offset entered by the user. The device under test will translate this frequency back to the frequency the receiver expects. Otherwise, phase locking and source operation occur as usual.

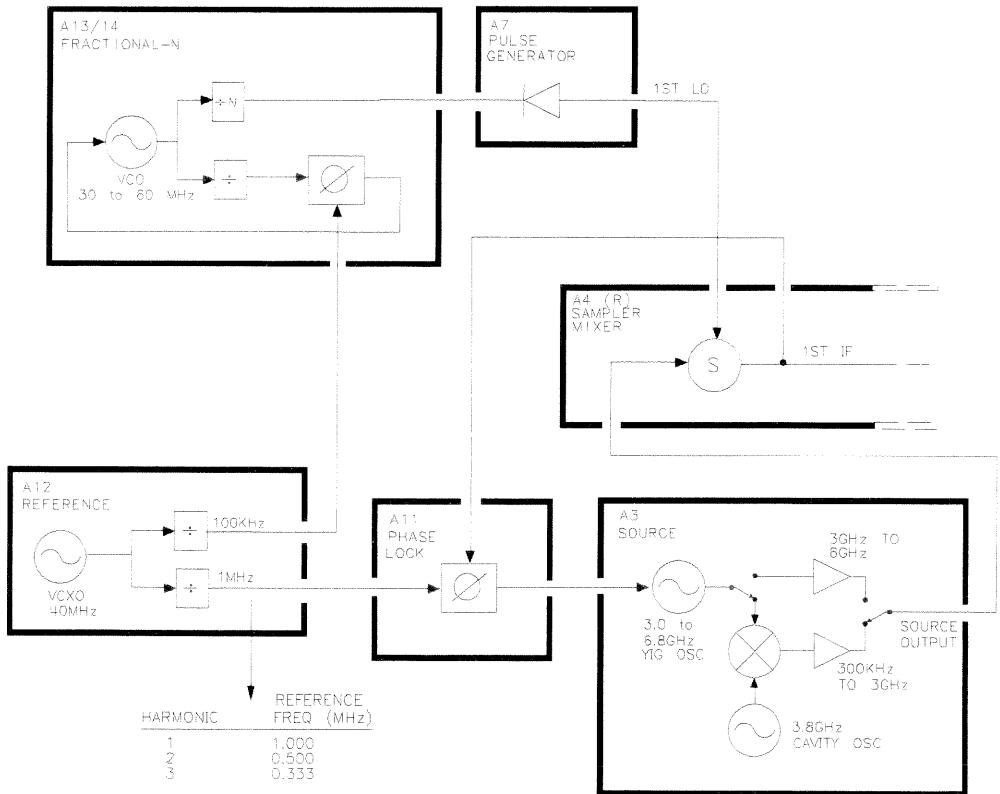
Harmonic Analysis (Option 002)

The analyzer can measure the 2nd or 3rd harmonic of the fundamental source frequency, on a swept or CW basis, with the harmonic analysis feature (optional).

To make this measurement, the reference frequency (normally 1 MHz) from the A12 reference assembly to the A11 phase lock assembly is divided by 1, 2, or 3. See Figure 12-6.

The fractional-N assemblies are also tuned so that the correct harmonic (comb tooth) of the 1st LO is 0.500 or 0.333 MHz below the source frequency instead of the usual 1.000 MHz. The analyzer pretunes the A3 source normally, then phase locks the 1st IF to the new reference frequency to sweep the fundamental source frequency in the usual way. The key difference is that the 1st IF (output from the R sampler) due to the fundamental and used for phase locking is now 0.500 or 0.333 MHz instead of 1.000 MHz.

Since the chosen VCO harmonic and the source differ by 0.500 or 0.333 MHz, then another VCO harmonic, 2 or 3 times higher in frequency, will be exactly 1.000 MHz away from the 2nd or 3rd harmonic of the source frequency. The samplers, then, will also down-convert these harmonics to yield the desired components in the 1st IF at 1.000 MHz. Narrow bandpass filters in the receiver eliminate all but the 1.000 MHz signals; these pass through to be processed and displayed.



sg6232d

Figure 12-6. Harmonic Analysis

External Source Mode

In external source mode, the analyzer phase locks its receiver to an external signal source. This source must be CW (not swept), but it does not need to be synthesized. The user must enter the source frequency into the analyzer. (The analyzer's internal source output is not used.)

To accomplish this, the phase lock loop is reconnected so that the tuning voltage from the A11 phase lock assembly controls the VCO of the A14 fractional-N assembly and not the A3 source. See Figure 12-7. The VCO's output still drives the 1st LO of the samplers and down-converts the RF signal supplied by the external source. The resulting 1st IF is fed back to the A11 phase lock assembly,

12-22 Theory of Operation

compared to the 1.000 MHz reference, and used to generate a tuning voltage as usual. However, the tuning voltage controls the VCO to lock on to the external source, keeping the 1st IF at exactly 1.000 MHz.

The analyzer normally goes through a pretune-acquire-track sequence to achieve phase lock. In external source mode, the fractional-N VCO pretunes as a closed-loop synthesizer referenced to the 100 kHz signal from the A12 reference assembly. Then, to acquire or track, a switch causes the VCO to be tuned by the A11 phase lock assembly instead. (Refer to the Overall Block Diagram at the end of Chapter 4, "Start Troubleshooting Here.")

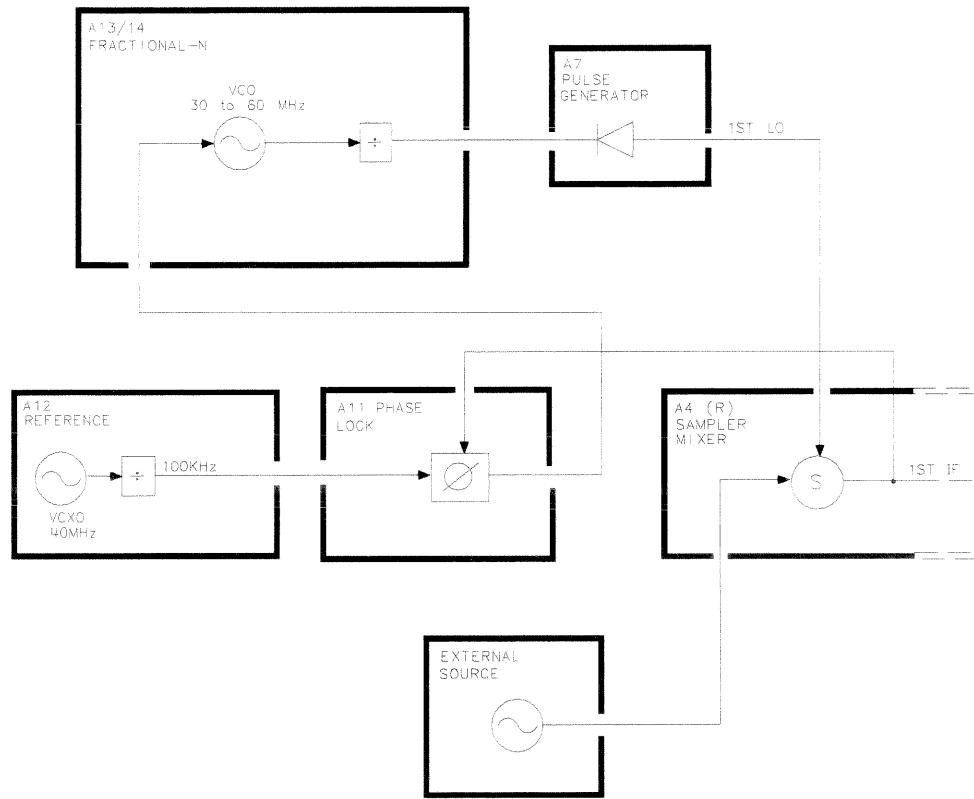


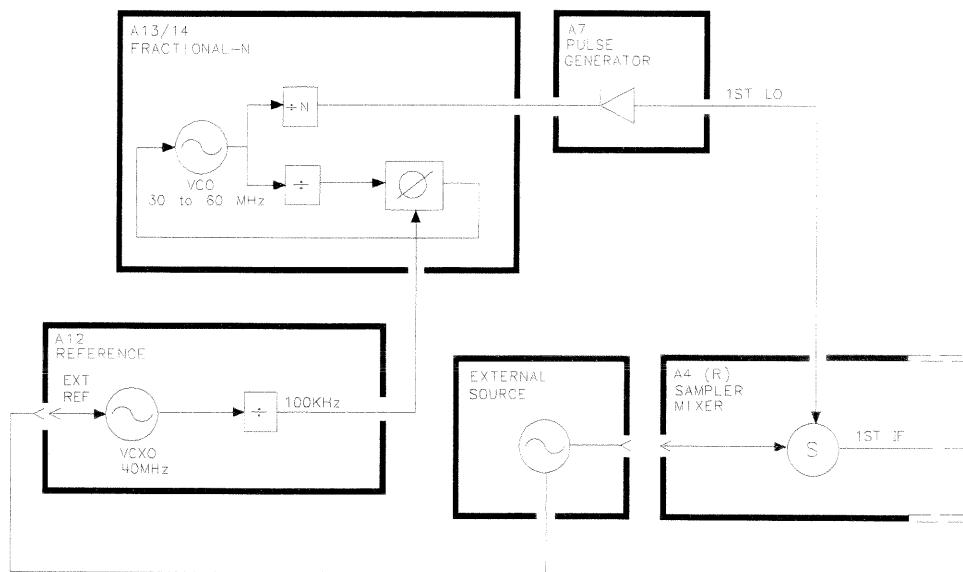
Figure 12-7. External Source Mode

Tuned Receiver Mode

In tuned receiver mode, the analyzer is a synthesized, swept, narrow-band receiver only. The external signal source must be synthesized and reference-locked to the analyzer.

To achieve this, the analyzer's source and phase lock circuits are completely unused. See Figure 12-8. The fractional-N synthesizer is tuned so that one of its harmonics (1st LO) down-converts the RF input to the samplers. (In contrast to external source mode, the analyzer does not phase lock at all. However, the 1st LO is synthesized.)

The analyzer can function as a swept tuned receiver, similar to a spectrum analyzer, but the samplers create spurious signals at certain frequencies, which limit the accuracy of such measurements.



sg6234d

Figure 12-8. Tuned Receiver Mode

12-24 Theory of Operation

Signal Separation

The Built-In Test Set

Figure 12-9 shows a simplified block diagram of the analyzer's built-in test set.

A21 and A22 Test Port Couplers

The analyzer's test port couplers are used to separate signals incident to, reflected from, and transmitted from the device under test. Each test port coupler has a coupling coefficient factor of 16 dB.

A23 LED Front Panel

The LED front panel board indicates whether the source power is incident on the analyzer's test port 1 or test port 2. The analyzer's source power is directed to test port 1 when making a forward transmission/reflection measurement. Similarly, source power is incident at test port 2 when making a reverse transmission/reflection measurement.

A24 Transfer Switch

The A3 source output power is directed to either the analyzer's test port 1 or test port 2 via a low loss solid state transfer switch. With this switch, all four S-parameters can be updated continuously (For example: the data obtained from a full 2-port calibration.) In addition, the transfer switch provides termination for the inactive test port in order to minimize the crosstalk between the source and receiver sampler.

A25 Test Set Interface

The test set interface board provides biasing for active devices under test with an external dc voltage. This dc voltage is applied directly to the test port center pin. In addition, the test set interface board provides the drive signal for the A24 forward/reverse transfer switch.

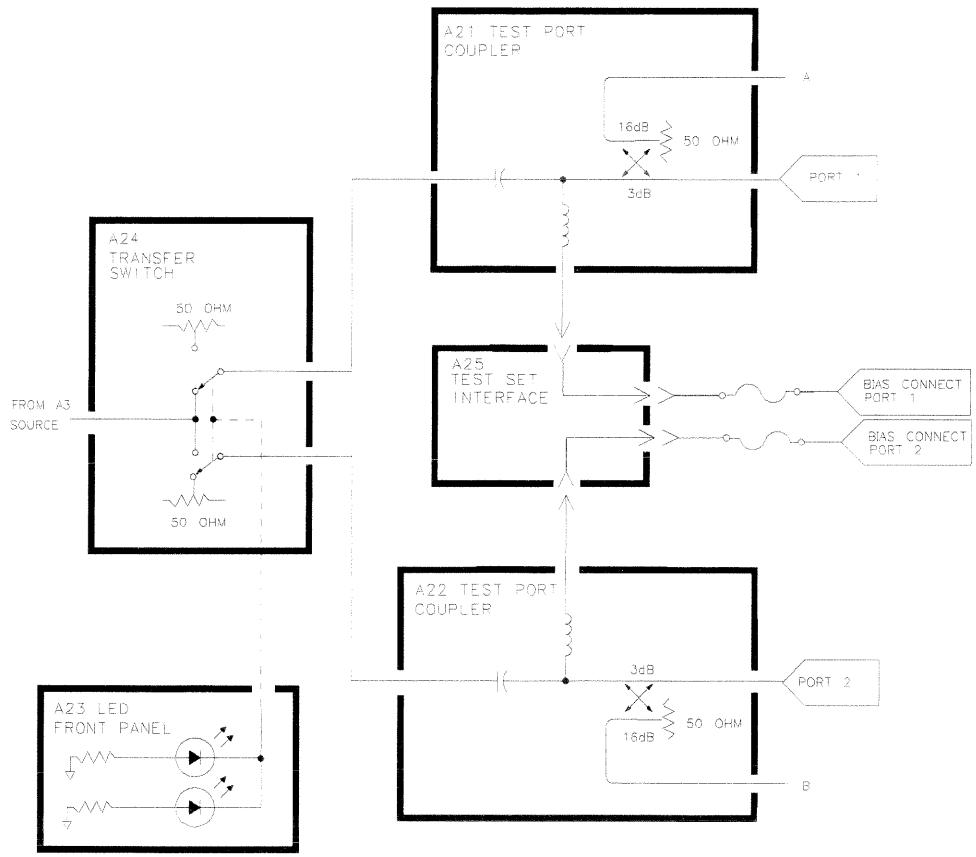


Figure 12-9. Simplified Block Diagram of the Built-in Test Set

12-26 Theory of Operation

Receiver Theory

The receiver functional group consists of the following assemblies:

A4 sampler/mixer

A5 sampler/mixer

A6 sampler/mixer

A10 digital IF

These assemblies combine with the A9 CPU (described in Digital Control Theory) to measure and process input signals into digital information for display on the analyzer. Figure 12-10 is a simplified block diagram of the receiver functional group. The A12 reference assembly is also included in the illustration to show how the 2nd LO signal is derived.

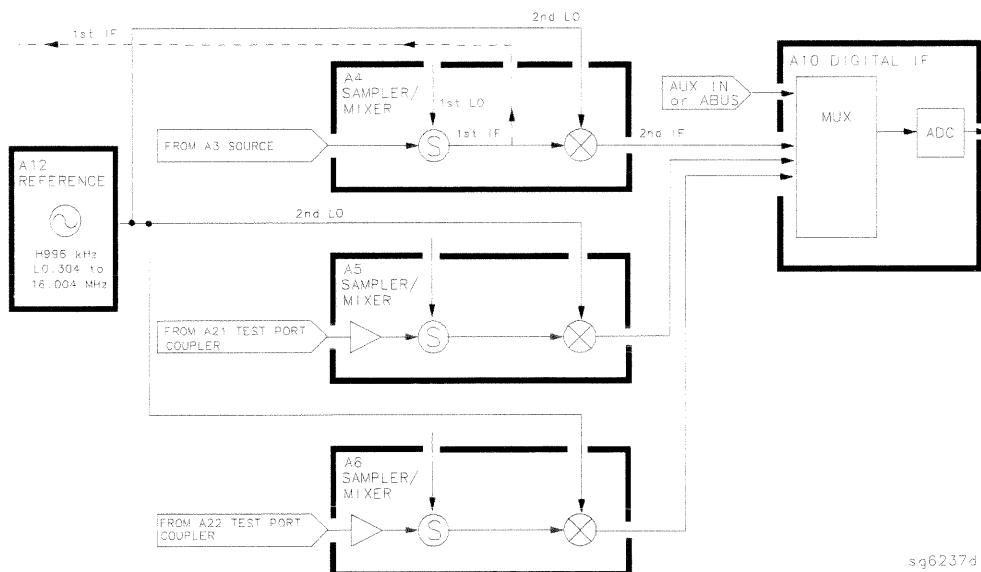


Figure 12-10. Receiver Functional Group, Simplified Block Diagram

A4/A5/A6 Sampler/Mixer

The A4, A5, and A6 sampler/mixers all down-convert the RF input signals to fixed 4 kHz 2nd IF signals with amplitude and phase corresponding to the RF input. The A5 and A6 sampler/mixer assemblies both include a 6 dB gain preamplifier in front of the sampler. This improves the noise figure performance of the analyzer's receiver channels A and B.

The Sampler Circuit in High Band

In high band operation, the sampling rate of the samplers is controlled by the 1st LO from the A7 pulse generator assembly. The 1st LO is a comb of harmonics produced by a step recovery diode driven by the fractional-N VCO fundamental signal. One of the harmonic signals is 1 MHz below the start frequency set at the front panel. The 1st LO is combined in the samplers with the RF input signal from the source. In the Option 006, samplers are additionally capable of recognizing RF input signals from 3 to 6 GHz. The mixing products are filtered, so that the only remaining response is the difference between the source frequency and the harmonic 1 MHz below it. This fixed 1 MHz signal is the 1st IF. Part of the 1st IF signal from the R sampler is fed back to the A11 phase lock assembly.

The Sampler Circuit in Low Band or Super Low Band

In low band or super low band the sampler diodes are biased continuously on, so that the RF input signal passes through them unchanged. Thus the 1st IF is identical to the RF output signal from the source (300 kHz to 16 MHz for lowband; 10 to 300 kHz for super lowband), and sweeps with it. Part of the 1st IF signal from the R sampler is fed back to the A11 phase lock assembly.

(Refer to "Source Theory Overview" for information on high band and low band operation of the source.)

The 2nd LO Signal

The 2nd LO is obtained from the A12 reference assembly. In high band, the 2nd LO is fixed at 996 kHz. This is produced by feeding the 39.84 MHz output of a phase-locked oscillator in the A12 assembly through a divide-by-40 circuit.

In low band, the 2nd LO is a variable frequency produced by mixing the output of the fractional-N VCO with a fixed 39.996 MHz signal in the A12 assembly. The 2nd LO covers the range of 0.014 to 16.004 MHz in two subsweeps that correspond with the source subsweeps. These subsweeps are 0.304 to 3.304 MHz and 3.304 to 16.004 MHz.

The Mixer Circuit

The 1st IF and the 2nd LO are combined in the mixer circuit. The resulting difference frequency (the 2nd IF) is a constant 4 kHz in both bands, as Table 12-4 shows.

Table 12-4. Mixer Frequencies

Band	1st IF	2nd LO	2nd IF
Super Low	0.010 to 0.300 MHz	0.014 to 0.304 MHz	4.0 kHz
Low	0.300 to 16.0 MHz	0.304 to 16.004 MHz	4.0 kHz
High	1.000 MHz	0.996 MHz	4.0 kHz

A10 Digital IF

The three 4 kHz 2nd IF signals from the sampler/mixer assemblies are input to the A10 digital IF assembly. These signals are sampled at a 16 kHz rate. A fourth input is the analog bus, which can monitor either an external input at the rear panel AUX IN connector, or one of 31 internal nodes. A multiplexer sequentially directs each of the signals to the ADC (analog-to-digital converter). Here they are converted to digital form and sent to the A9 CPU assembly for processing. Refer to "Digital Control Theory" for more information on signal processing.

13

Replaceable Parts

This chapter contains information for ordering replacement parts for the HP 8753D network analyzer. Replaceable parts include the following:

- major assemblies
- cables
- chassis hardware

In general, parts of major assemblies are not listed. Refer to Table 13-1 at the back of this chapter to help interpret part descriptions in the replaceable parts lists that follow.

Replacing an assembly

The following steps show the sequence to replace an assembly in an HP 8753D network analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Rebuilt-Exchange Assemblies

Under the rebuilt-exchange assembly program, certain factory-repaired and tested modules (assemblies) are available on a trade-in basis. These assemblies are offered for lower cost than a new assembly, but meet all factory specifications required of a new assembly.

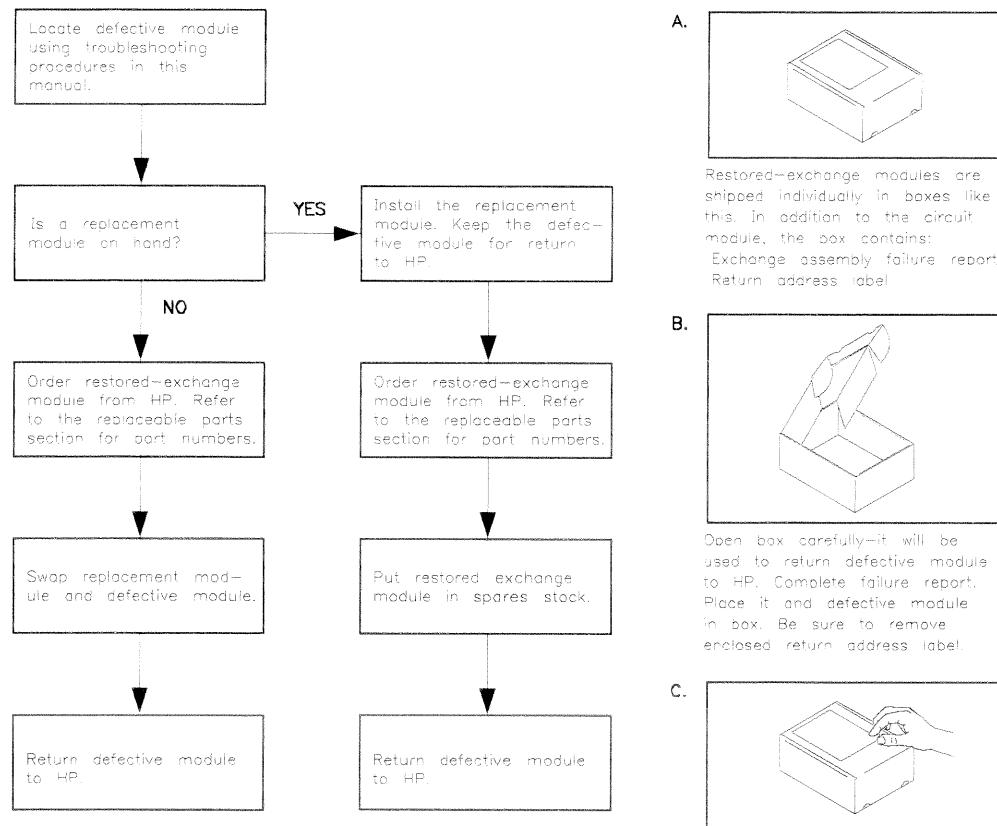
The defective assembly must be returned for credit under the terms of the rebuilt-exchange assembly program. Any spare assembly stock desired should be ordered using the new assembly part number. Figure 13-1 illustrates the module exchange procedure. "Major Assemblies, Top" and "Major Assemblies, Bottom" list all major assemblies, including those that can be replaced on an exchange basis.

Ordering Information

To order a part listed in the replaceable parts lists, quote the Hewlett-Packard part number, indicate the quantity required, and address the order to the nearest Hewlett-Packard Sales and Service office.

To order a part that is not listed in the replaceable parts lists, include the instrument model number, complete instrument serial number, the description and function of the part, and the number of parts required. Address the order to the nearest Hewlett-Packard Sales and Service Office.

The module exchange program described here is a fast, efficient, economical method of keeping your Hewlett-Packard instrument in service.



*HP pays postage on boxes mailed in U.S.A.

sg613d

Figure 13-1. Module Exchange Procedure

13-4 Replaceable Parts

Replaceable Part Listings

The following pages list the replacement part numbers and descriptions for the HP 8753D Network Analyzer. Illustrations with reference designators are provided to help identify and locate the part needed. The parts lists are organized into the following categories:

- Major Assemblies, Top
- Major Assemblies, Bottom
- Cables, Top
- Cables, Bottom
- Cables, Front
- Cables, Rear
- Cables, Source
- Front Panel, Outside
- Front Panel, Inside
- Rear Panel
- Rear Panel, Option 1D5
- Hardware, Top
- Hardware, Bottom
- Hardware, Front
- Hardware, Test Set Deck
- Hardware, Disk Drive Support
- Hardware, Memory Deck
- Hardware, Fan
- Hardware, Preregulator
- Chassis Parts, Outside
- Chassis Parts, Inside
- Miscellaneous

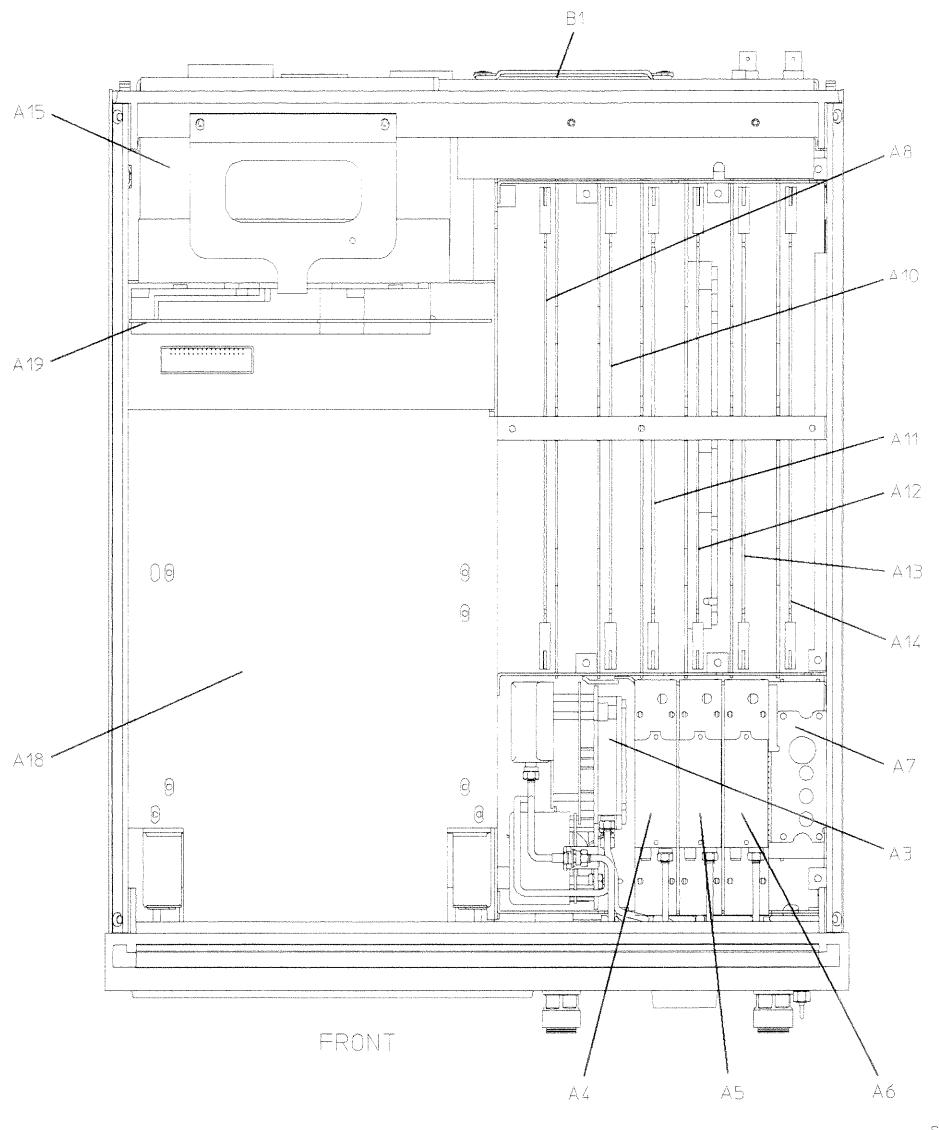
Major Assemblies, Top

Ref. Desig.	Option	HP Part Number	Qty	Description
A1				NOT SHOWN (see "Front Panel Assembly, Inside")
A2				NOT SHOWN (see "Front Panel Assembly, Inside")
A3		08753-60231	1	ASSY-SOURCE 3 GHz
A3		08753-69231	1	ASSY-SOURCE 3 GHz (REBUILT-EXCHANGE)
A3	006	08753-60146	1	ASSY-SOURCE 6 GHz
A3	006	08753-69146	1	ASSY-SOURCE 6 GHz (REBUILT-EXCHANGE)
A4		08753-60004	1	ASSY-SAMPLER R
A4		08753-69004	1	ASSY-SAMPLER R (REBUILT-EXCHANGE)
A5		08753-60169	1	ASSY-SAMPLER A
A5		08753-69169	1	ASSY-SAMPLER A (REBUILT-EXCHANGE)
A6		08753-60169	1	ASSY-SAMPLER B
A6		08753-69169	1	ASSY-SAMPLER B (REBUILT-EXCHANGE)
A7		08753-60164	1	BD ASSY-PULSE GENERATOR
A7		08753-69164	1	BD ASSY-PULSE GENERATOR (REBUILT-EXCHANGE)
A8*		08753-60208	1	BD ASSY-POST REGULATOR
A10		08753-60095	1	BD ASSY-DIGITAL IF
A11		08753-60162	1	BD ASSY-PHASE LOCK
A12		08753-60209	1	BD ASSY-REFERENCE
A13		08753-60013	1	BD ASSY-FRAC N ANALOG
A14		08753-60068	1	BD ASSY-FRAC N DIGITAL
A15		08753-60098	1	ASSY-PREREULATOR
A15		08753-69098	1	ASSY-PREREULATOR (REBUILT-EXCHANGE)
A16				NOT SHOWN (see "Rear Panel Assembly")
A17				NOT SHOWN (see "Chassis Parts, Inside")
A18		5180-8484	1	ASSY-DISPLAY (REBUILT-EXCHANGE)
A19		08753-60170	1	BD ASSY-Graphics PROCESSOR
A26	1D5			NOT SHOWN (see "Rear Panel Assembly, Option 1D5")
B1		08753-60047	1	ASSY-FAN
RPG1				NOT SHOWN (see "Front Panel Assembly, Outside")

* For fuse part numbers on the A8 Post Regulator refer to "Miscellaneous" in this chapter.

13-6 Replaceable Parts

Major Assemblies, Top



sg675d

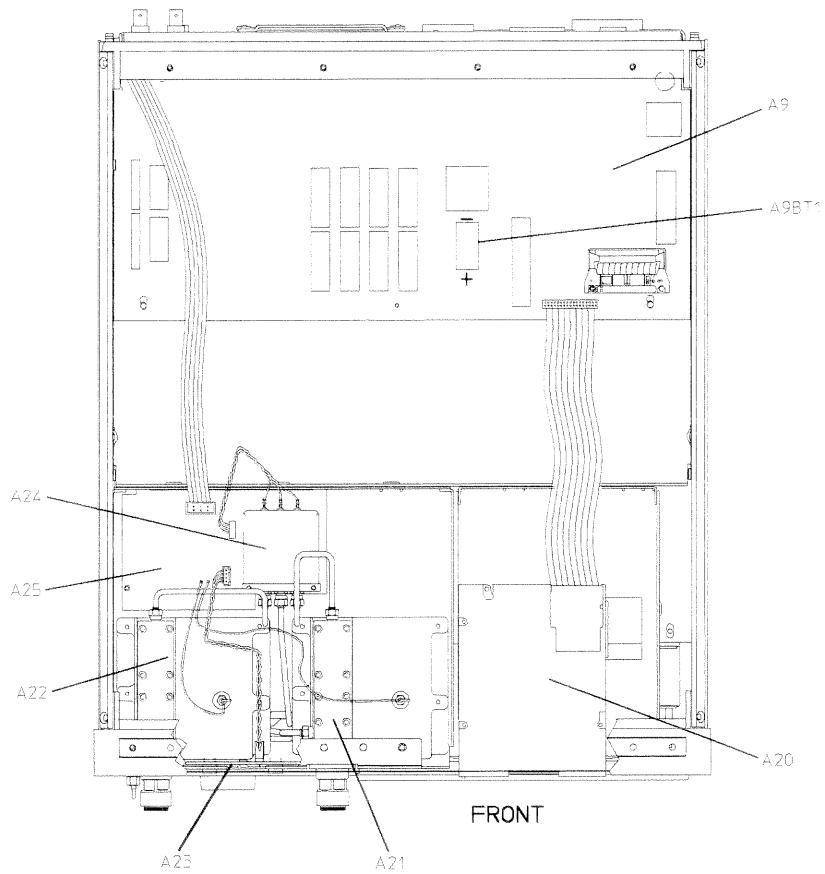
Replaceable Parts 13-7

Major Assemblies, Bottom

Ref. Desig.	Option	HP Part Number	Qty	Description
A9		08753-60219	1	BD ASSY-CPU
A9BT1		1420-0338	1	BATTERY-LITHIUM 3V 1.2AH
A20		0950-2348	1	ASSY-DISK DRIVE
A21		5086-7489	1	ASSY-TEST PORT COUPLER
A21		5086-6489	1	ASSY-TEST PORT COUPLER (REBUILT-EXCHANGE)
A21	075	5086-7651	1	ASSY-TEST PORT COUPLER
A21	075	5086-6651	1	ASSY-TEST PORT COUPLER (REBUILT-EXCHANGE)
A22		5086-7489	1	ASSY-TEST PORT COUPLER
A22		5086-6489	1	ASSY-TEST PORT COUPLER (REBUILT-EXCHANGE)
A22	075	5086-7651	1	ASSY-TEST PORT COUPLER
A22	075	5086-6651	1	ASSY-TEST PORT COUPLER (REBUILT-EXCHANGE)
A23		08753-60145	1	BD ASSY-LED FRONT PANEL
A24		5086-7539	1	ASSY-TRANSFER SWITCH
A24		5086-6539	1	ASSY-TRANSFER SWITCH (REBUILT-EXCHANGE)
A25		08753-60144	1	BD ASSY-TEST SET INTERFACE

13-8 Replaceable Parts

Major Assemblies, Bottom



sg674d

Replaceable Parts 13-9

Cables, Top

Ref. Desig.	Type *	Opt	HP Part Number	Qty	Description
A15W1	18W		(part of A15)	1	PREREGULATOR (A15) to POST REGULATOR (A8J2) and MOTHERBOARD (A17J3)
A18W1	20R		(part of A18)	1	DISPLAY (A18) to GRAPHICS PROCESSOR (A19J5)
W1	SR		08753-20098	1	SOURCE ASSY (A3W4) to TRANSFER SWITCH (A24)
W2	SR		08753-20221	1	FP (R CHANNEL IN) to SAMPLER-R (A4)
W3	SR		08753-20099	1	TEST PORT 1 COUPLER (A21) to SAMPLER-A (A5)
W4	SR		08753-20100	1	TEST PORT 2 COUPLER (A22) to SAMPLER-B (A6)
W5	F		08753-60027	1	SAMPLER-R (A4) to PULSE GENERATOR (A7)
W6	F		08753-60027	1	SAMPLER-A (A5) to PULSE GENERATOR (A7)
W7	F		08753-60027	1	SAMPLER-B (A6) to PULSE GENERATOR (A7)
W8	F		08753-60061	1	PHASE LOCK (A11J1) to SAMPLER-R (A4)
W9	F		08753-60061	1	FRAC-N DIGITAL (A14J1) to PULSE GENERATOR (A7)
W10	F		08753-60029	1	FRAC-N DIGITAL (A14J2) to REFERENCE (A12J1)
W11	F		08753-60029	1	FRAC-N DIGITAL (A14J3) to FRAC-N ANALOG (A13J1)
W12	F		08753-60029	1	FRAC-N ANALOG (A13J2) to REFERENCE (A12J2)
W13	F		08753-60026	1	REFERENCE (A12J3) to RP (EXT REF)
W14	6W		08753-60113	1	POST REGULATOR (A8J1) to GRAPHICS PROCESSOR (A19J4)
W20	34R		8120-6381	1	CPU (A9J5) to GRAPHICS PROCESSOR (A19J6)
W24	SR		08753-20220	1	SOURCE ASSY (A3) to FP (R CHANNEL OUT)
W26	F		8120-5022	1	SOURCE ASSY (A3) to REFERENCE (A12J4)

* nW Wire Bundle (n is the number of wires in the bundle)

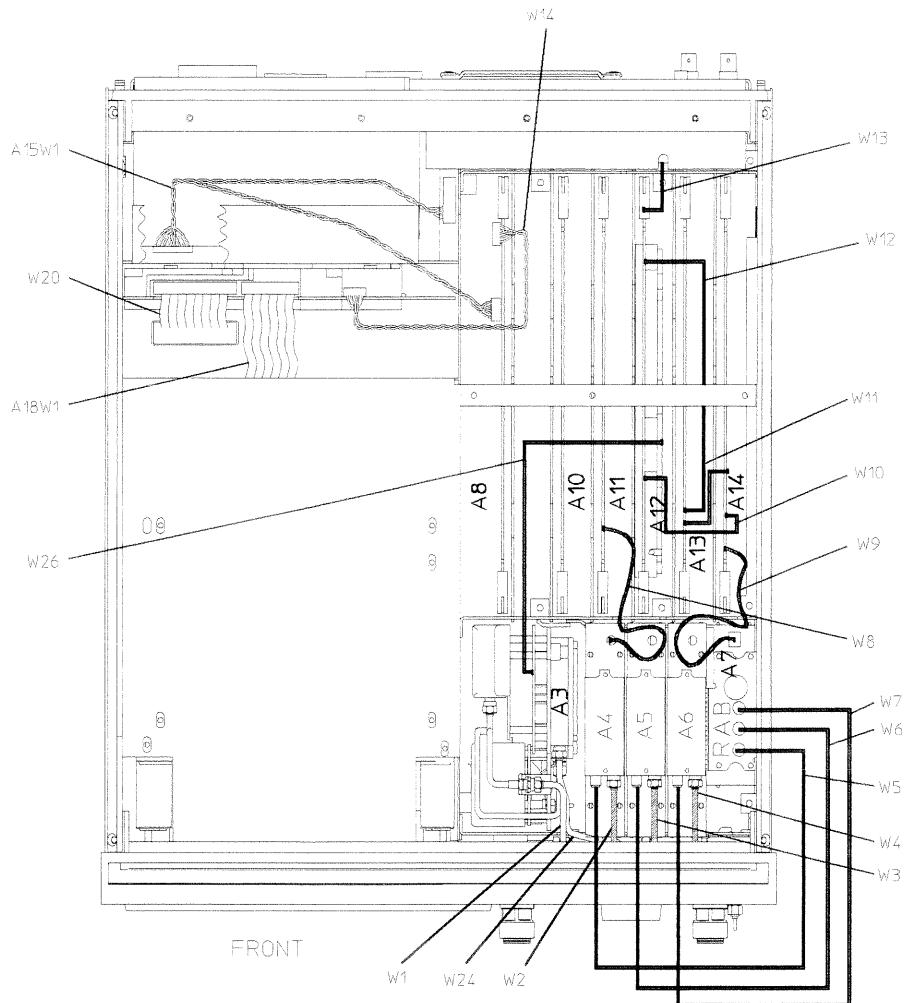
nR Ribbon Cable (n is the number of wires in the ribbon)

F Flexible Coax Cable

SR Semi-Rigid Coax Cable

13-10 Replaceable Parts

Cables, Top



sg676d

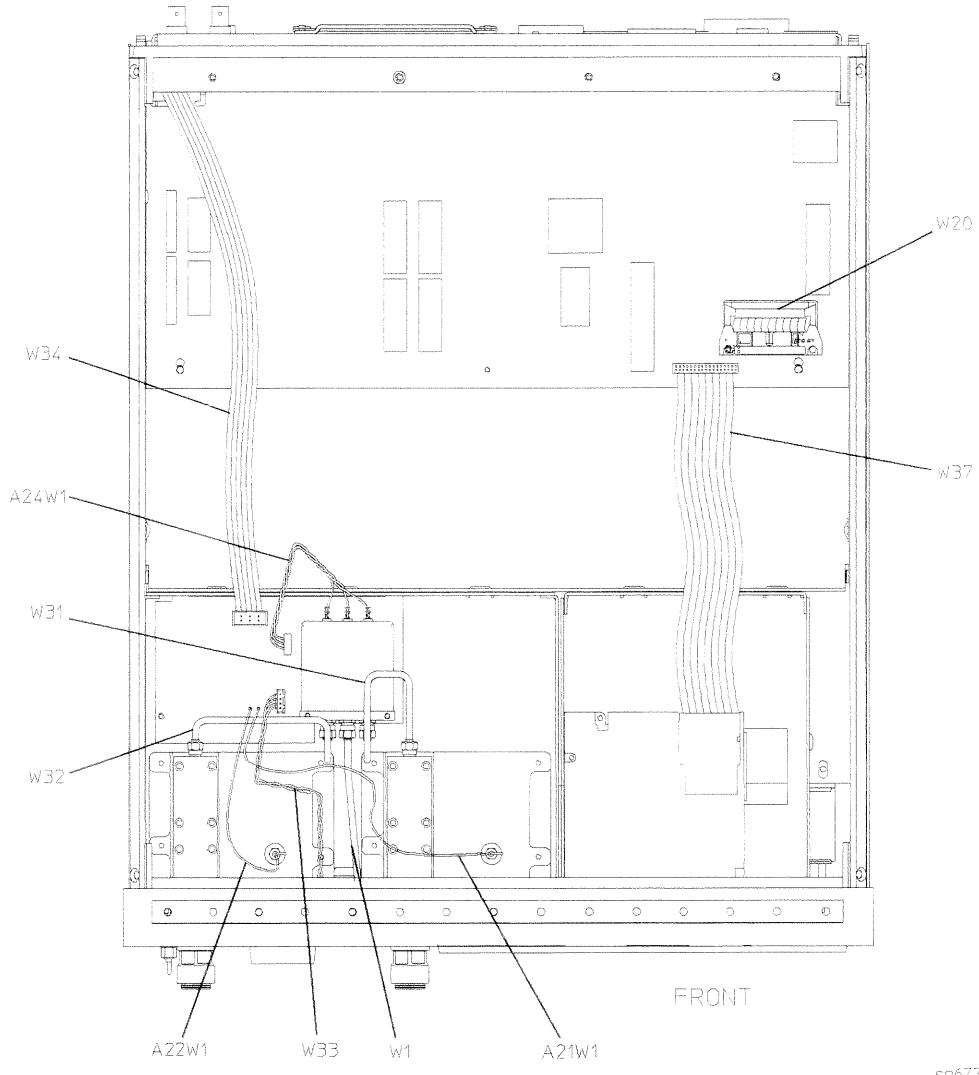
Cables, Bottom

Ref. Desig.	Type*	Opt	HP Part Number	Qty	Description
A21W1	1W		8120-6484	1	BLUE WIRE-TEST PORT 1 COUPLER (A21) to TEST SET INTERFACE (A25TP1)
A22W1	1W		8120-6483	1	GRAY WIRE-TEST PORT 2 COUPLER (A22) to TEST SET INTERFACE (A25TP2)
A24W1	3W		85047-60004	1	TRANSFER SWITCH (A24) to TEST SET INTERFACE (A25J3)
W1	SR		08753-20098	1	SOURCE ASSY (A3W4) to TRANSFER SWITCH (A24)
W20	34R		8120-6381	1	CPU (A9J5) to GRAPHICS PROCESSOR (A19J6)
W31	SR		08753-20101	1	TEST PORT 1 COUPLER (A21) to TRANSFER SWITCH (A24)
W32	SR		08753-20102	1	TEST PORT 2 COUPLER (A22) to TRANSFER SWITCH (A24)
W33	4W		08753-60221	1	LED (A23J1) to TEST SET INTERFACE (A25J2)
W34	10R		8120-6380	1	TEST SET INTERFACE (A25J1) to RP INTERFACE (A16J5)
W37	26R		8120-6432	1	DISK DRIVE (A20) to CPU (A9J15)

* nW Wire Bundle (n is the number of wires in the bundle)
 nR Ribbon Cable (n is the number of wires in the ribbon)
 SR Semi-Rigid Coax Cable

13-12 Replaceable Parts

Cables, Bottom



sg677d

Cables, Front

Ref. Desig.	Type*	Opt	HP Part Number	Qty	Description
A1W1	26R		08753-60036	1	FP KEYBOARD (A1J1) to FP INTERFACE (A2J2)
RPG1W1	5R		(part of RPG1)	1	RPG to FP INTERFACE (A2J5)
W1	SR		08753-20098	1	SOURCE ASSY (A3W4) to TRANSFER SWITCH (A24)
W2	SR		08753-20221	1	FP (R CHANNEL IN) to SAMPLER-R (A4)
W3	SR		08753-20099	1	TEST PORT 1 COUPLER (A21) to SAMPLER-A (A5)
W4	SR		08753-20100	1	TEST PORT 2 COUPLER (A22) to SAMPLER-B (A6)
W17	26R		08753-60037	1	FP INTERFACE (A2J1) to MOTHERBOARD (A17J1)
W18	3W		08711-60037	1	FP INTERFACE (A2J4) to FP (PROBE POWER)
W19	3W		08711-60037	1	FP INTERFACE (A2J3) to FP (PROBE POWER)
W24	SR		08753-20220	1	SOURCE ASSY (A3) to FP (R CHANNEL OUT)
W25	SR		08720-20075	1	FP (R CHANNEL OUT) to FP (R CHANNEL IN)

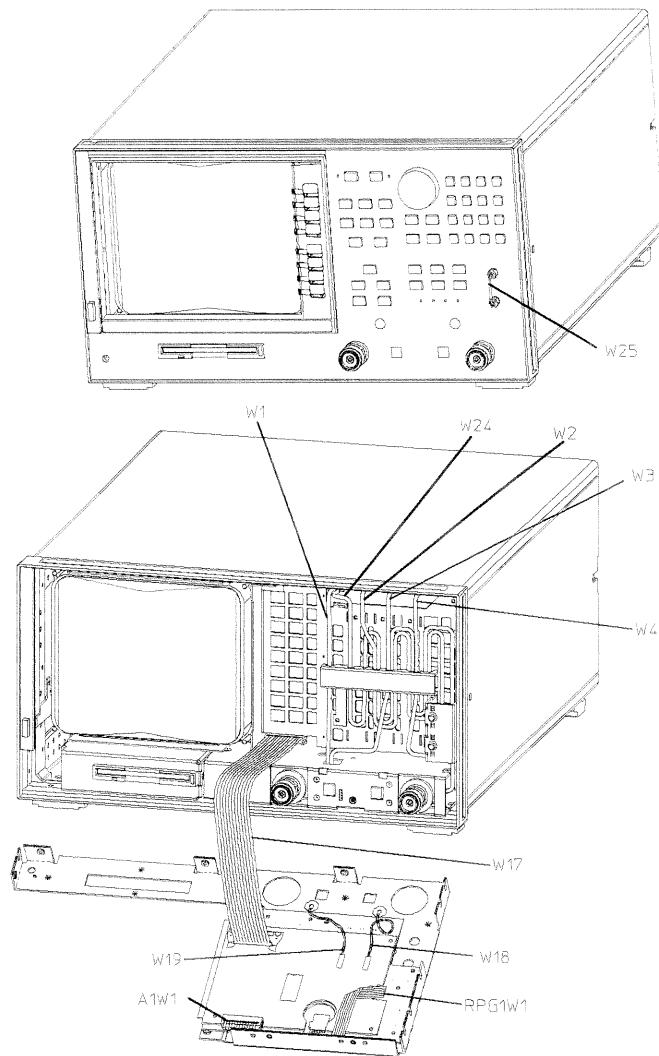
* nW Wire Bundle (*n* is the number of wires in the bundle)

nR Ribbon Cable (*n* is the number of wires in the ribbon)

SR Semi-Rigid Coax Cable

13-14 Replaceable Parts

Cables, Front



sg678d

Replaceable Parts 13-15

Cables, Rear

Ref. Desig.	Type*	Opt	HP Part Number	Qty	Description
B1W1	2W		(part of B1)	1	FAN (B1) to MOTHERBOARD (A17J5)
W13	F		08753-60026	1	REFERENCE (A12J3) to RP (EXT REF)
W21	F		8120-5055	1	GRAPHICS PROCESSOR (A19J1) to RP (EXT MON - RED)
W22	F		8120-5055	1	GRAPHICS PROCESSOR (A19J2) to RP (EXT MON - GREEN)
W23	F		8120-5055	1	GRAPHICS PROCESSOR (A19J3) to RP (EXT MON - BLUE)
W27	34R		8120-6407	1	RP INTERFACE (A16J4) to MOTHERBOARD (A17J6)
W28	2W		85047-60005	1	RP INTERFACE (A16J10) to RP (PORT 1 FUSE)
W29	2W		85047-60005	1	RP INTERFACE (A16J11) to RP (PORT 2 FUSE)
W30	3W	1D5	8120-6458	1	RP INTERFACE (A16J3) to HIGH-STABILITY FREQ REF (A26J1)
W34	10R		8120-6380	1	TEST SET INTERFACE (A25J1) to RP INTERFACE (A16J5)
W35	50R		8120-6379	1	CPU (A9J1) to MOTHERBOARD (A17J7)
W36	26R		8120-6382	1	CPU (A9J2) to MOTHERBOARD (A17J8)

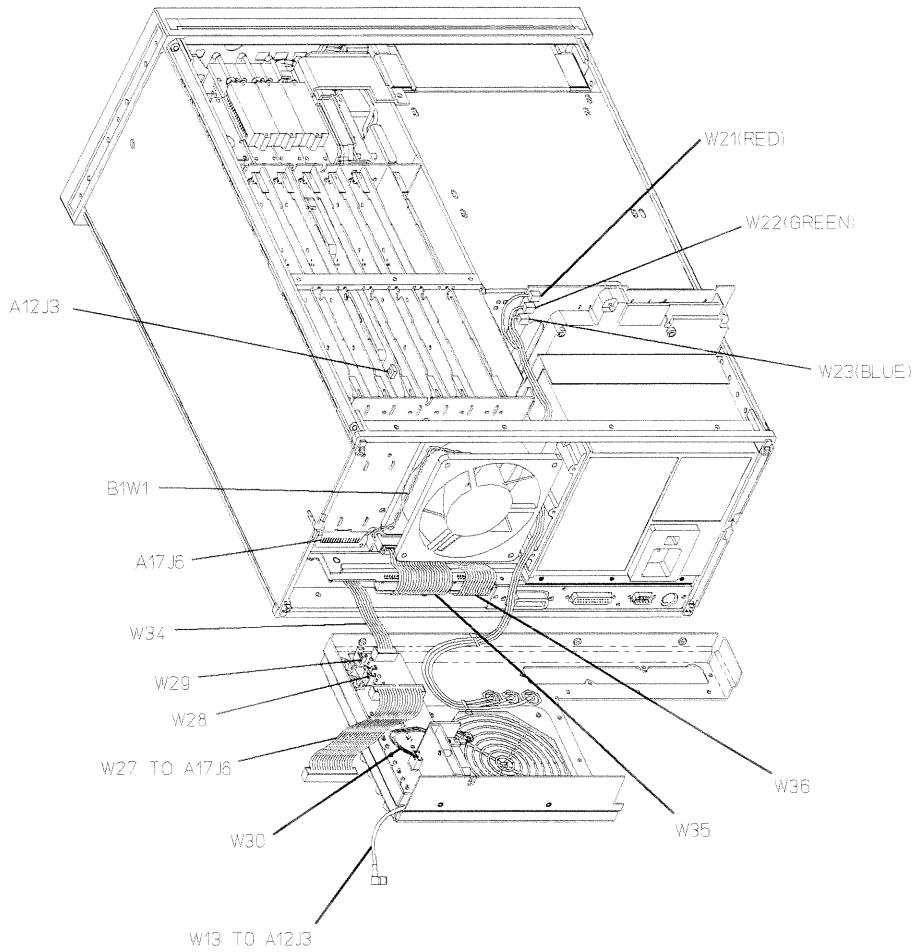
* nW Wire Bundle (*n* is the number of wires in the bundle)

nR Ribbon Cable (*n* is the number of wires in the ribbon)

F Flexible Coax Cable

13-16 Replaceable Parts

Cables, Rear



sg679d

Cables, Source

Ref. Desig.	Type*	Opt	HP Part Number	Qty	Description
A3A2W1	10R		08753-60034	1	EYO (A3A3) to ALC (A3A2J3)
A3A4W1	4W		08753-60035	1	CAVITY OSC (A3A4) to ALC (A3A2J2)
A3W1	SR		08753-20107	1	EYO (A3A3) to SOURCE ASSY (A3)
A3W2	SR		08753-20032	1	CAVITY OSC (A3A4) to SOURCE ASSY (A3)
A3W3	SR		08753-20106	1	SOURCE ASSY (A3) to ATTENUATOR (A3A5)
A3W4	SR		08753-20111	1	ATTENUATOR (A3A5) to W1
A3W5	10R		5062-0701	1	ALC (A3A2J1) to ATTENUATOR (A3A5)

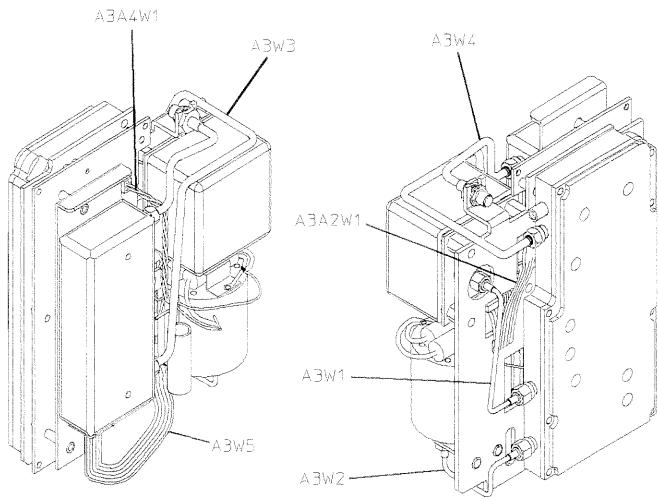
* nW Wire Bundle (*n* is the number of wires in the bundle)

nR Ribbon Cable (*n* is the number of wires in the ribbon)

SR Semi-Rigid Coax Cable

13-18 Replaceable Parts

Cables, Source



RIGHT TOP FRONT

LEFT TOP BACK

sg673d

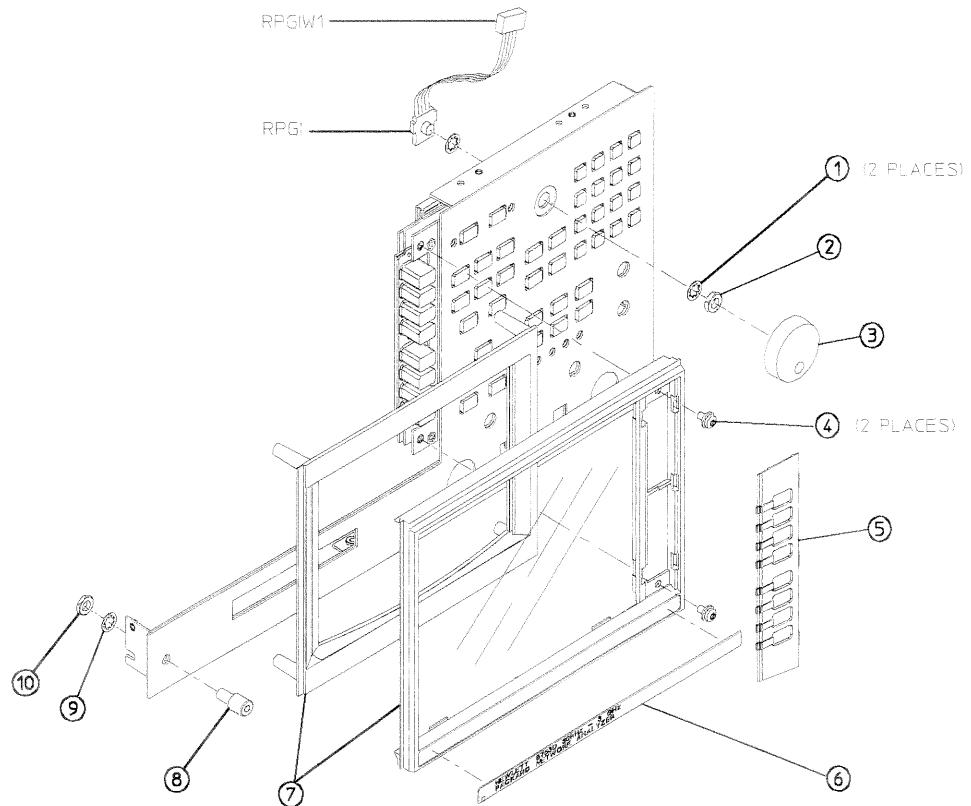
Replaceable Parts 13-19

Front Panel Assembly, Outside

Ref. Desig.	Option	HP Part Number	Qty	Description
1		2190-0016	2	WASHER-LOCK .377ID
2		2950-0043	1	NUT-HEX 3/8-32
3		01650-47401	1	KNOB-RPG
4		0515-2113	2	SCREW-MACHINE M4.0×8 PC-PN-TX
5		08757-40012	1	COVER-MENU BUTTON
6		08753-80125	1	NAMEPLATE-8753D
6	006	08753-80126	1	NAMEPLATE-8753D OPTION 006
7		5062-7208	1	ASSEMBLY-BEZEL (<i>nameplate must be ordered separately</i>)
8		1510-0038	1	BINDER POST ASSY
9		2190-0067	1	WASHER-LOCK .256ID
10		2950-0006	1	NUT-HEX 1/4-32
RPG1		1990-1525	1	RPG-MINIATURE
RPG1W1		(part of RPG1)	1	RPG to FP INTERFACE (A2J5)

13-20 Replaceable Parts

Front Panel Assembly, Outside



sg680d

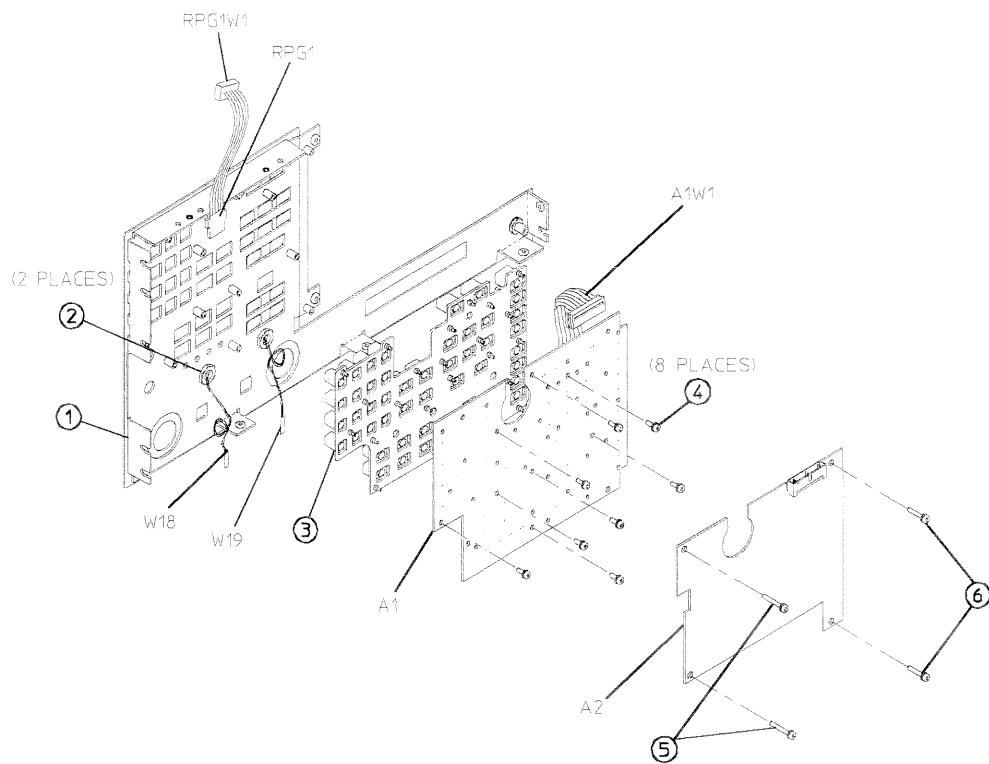
Replaceable Parts 13-21

Front Panel Assembly, Inside

Ref. Desig.	Option	HP Part Number	Qty	Description
1		08753-60182	1	PANEL ASSY-DRESS 8753D
1	075	08753-60184	1	PANEL ASSY-DRESS 8753D #075
2		2950-0144	2	NUT-HEX 3/8-32
3		08753-40011	1	KEYPAD-RUBBER
4		0515-0374	8	SCREW-MACHINE M3.0×10 CW-PN-TX
5		0515-1410	2	SCREW-MACHINE M3.0×20 CW-PN-TX
6		0515-0375	2	SCREW-MACHINE M3.0×16 CW-PN-TX
A1		08753-60217	1	BD ASSY-KEYBOARD
A1W1		08753-60036	1	FP KEYBOARD (A1J1) to FP INTERFACE (A2J2)
A2		08753-60091	1	BD ASSY-FRONT PANEL INTERFACE
RPG1		1990-1525	1	RPG-MIN
RPG1W1		(part of RPG1)	1	RPG to FP INTERFACE (A2J5)
W18		08711-60037	1	FP INTERFACE (A2J4) to FP (PROBE POWER)
W19		08711-60037	1	FP INTERFACE (A2J3) to FP (PROBE POWER)

13-22 Replaceable Parts

Front Panel Assembly, Inside



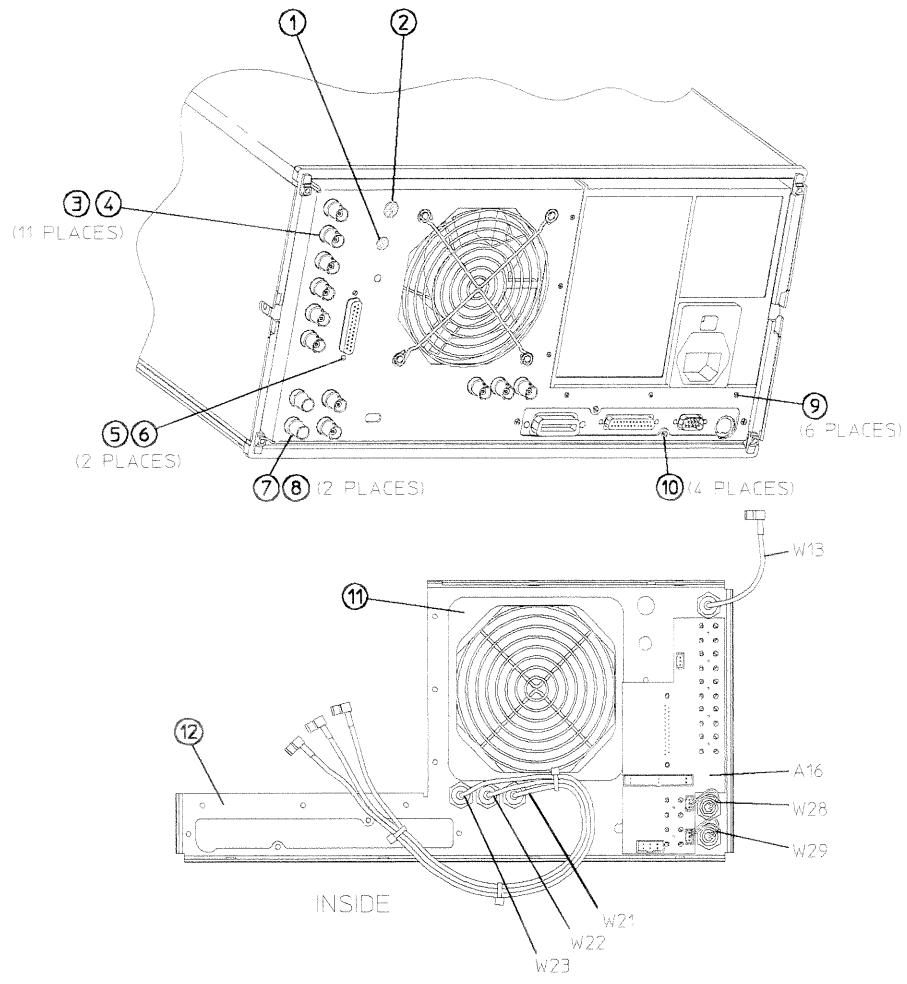
sg681d

Rear Panel Assembly

Ref. Desig.	Option	HP Part Number	Qty	Description
1		6960-0086	1	PLUG-HOLE .375D NY BLACK
2		6960-0149	1	PLUG-HOLE .5D NY BLACK
3		2950-0035	11	NUT-HEX 15/32-32
4		2190-0102	11	WASHER-LOCK .472ID
5		1251-7812	2	CONNECTOR JACKSCREW
6		2190-0584	2	WASHER-LOCK M3.0 NOM
7		1400-0112	2	CAP-FUSE HOLDER 5A 125V
8		2110-0047	2	FUSE 1A 125V NON-TIME DELAY
9		0515-0372	6	SCREW-MACHINE M3.0×8 CW-PN-TX
10		0515-0372	4	SCREW-MACHINE M3.0×8 CW-PN-TX
11		08753-20040	1	GASKET-FAN
12		08753-00066	1	PANEL-REAR
A16		08753-60218	1	BD ASSY-REAR PANEL
W13		08753-60026	1	REFERENCE (A12J3) to RP (EXT REF)
W21		8120-5055	1	GRAPHICS PROCESSOR (A19J1) to RP (EXT MON - RED)
W22		8120-5055	1	GRAPHICS PROCESSOR (A19J2) to RP (EXT MON - GREEN)
W23		8120-5055	1	GRAPHICS PROCESSOR (A19J3) to RP (EXT MON - BLUE)
W28		85047-60005	1	RP INTERFACE (A16J10) to RP (PORT 1 FUSE)
W29		85047-60005	1	RP INTERFACE (A16J11) to RP (PORT 2 FUSE)

13-24 Replaceable Parts

Rear Panel Assembly



sg683d

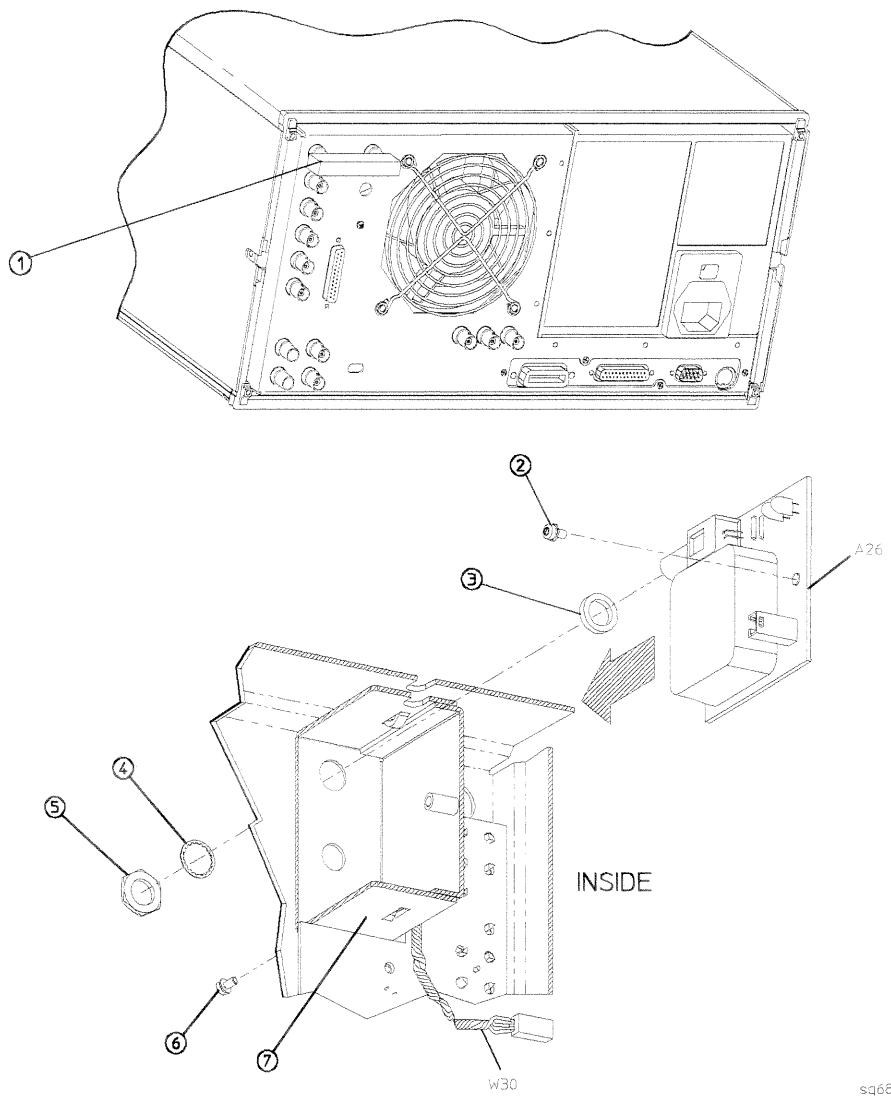
Replaceable Parts 13-25

Rear Panel Assembly, Option 1D5

Ref. Desig.	Option	HP Part Number	Qty	Description
1	1D5	1250-1859	1	ADAPTER-COAX
2	1D5	0515-0374	1	SCREW-MACHINE M3.0×10 CW-PN-TX
3	1D5	3050-1546	1	WASHER-FLAT .505ID NY
4	1D5	2190-0068	1	WASHER-LOCK .505ID
5	1D5	0590-1310	1	NUT-SPECIALTY 1/2-28
6	1D5	0515-0430	1	SCREW-MACHINE M3.0×6 CW-PN-TX
7	1D5	08753-00078	1	BRACKET-OSC BD
A26	1D5	08753-60158	1	BD ASSY-HIGH STABILITY FREQ REF
W30	1D5	8120-6458	1	RP INTERFACE (A16J3) to HIGH-STABILITY FREQ REF (A26J1)

13-26 Replaceable Parts

Rear Panel Assembly, Option 1D5



sg682d

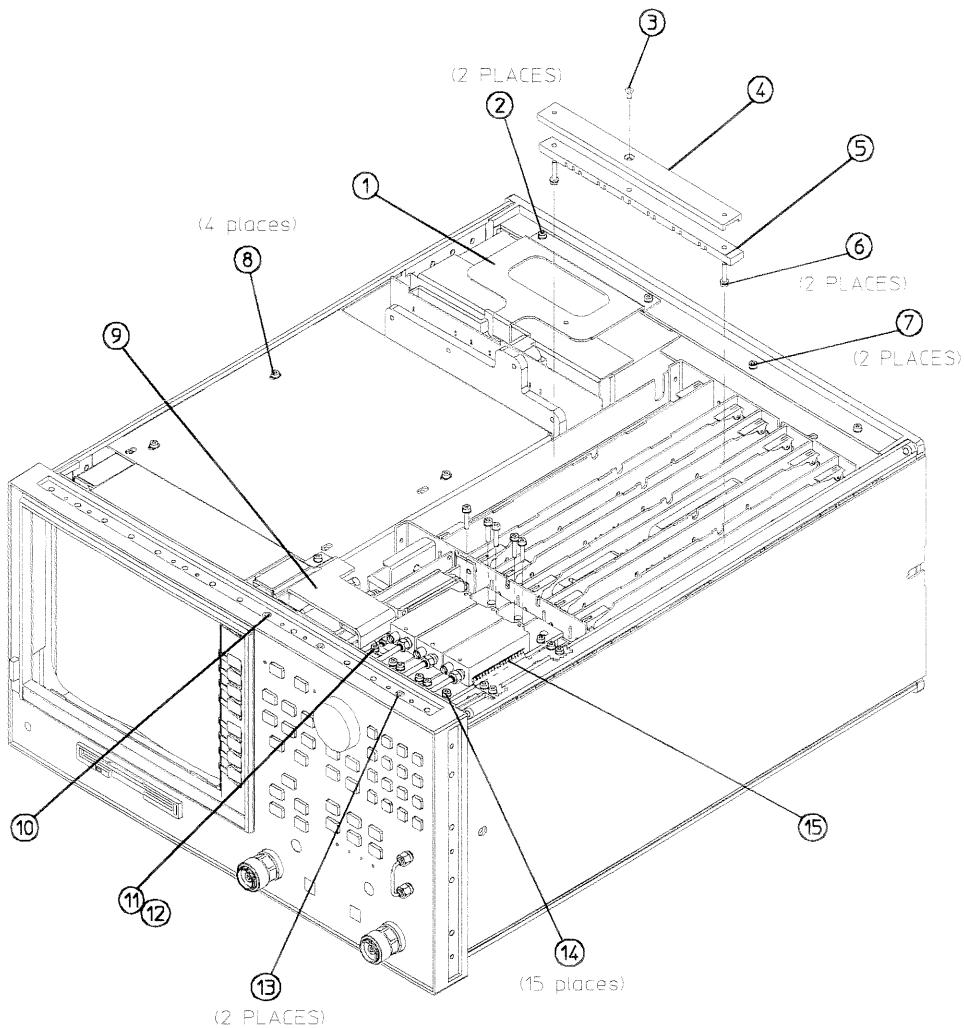
Replaceable Parts 13-27

Hardware, Top

Ref. Desig.	Option	HP Part Number	Qty	Description
1		5181-5525	1	CLIP (bracket securing A19 board)
2		0515-0377	2	SCREW-MACHINE M3.5×10 CW-PN-TX
3		0515-2035	1	SCREW-MACHINE M3.0×16 PC-FL-TX
4		08753-20062	1	STABILIZER CAP
5		08753-40005	1	STABILIZER-PC BOARD
6		0515-0374	2	SCREW-MACHINE M3.0×10 CW-FL-TX
7		0515-0458	2	SCREW-MACHINE M3.5×8 CW-PN-TX
8		0515-0483	4	SCREW-MACHINE M4.0×8 CW-FL-TX
9		08753-00054	1	BRACKET-SOURCE
10		0515-2086	1	SCREW-MACHINE M4.0×7 PC-FL-TX
11		0515-0664	1	SCREW-MACHINE M3.0×12 CW-PN-TX
12		3050-0891	1	WASHER-FLAT M3.0 NOM
13		0515-1400	2	SCREW-MACHINE M3.5×8 PC-FL-TX
14		0515-0374	15	SCREW-MACHINE M3.0×10 CW-PN-TX
15		08753-00040	1	CLIP-PULSER GROUND

13-28 Replaceable Parts

Hardware, Top



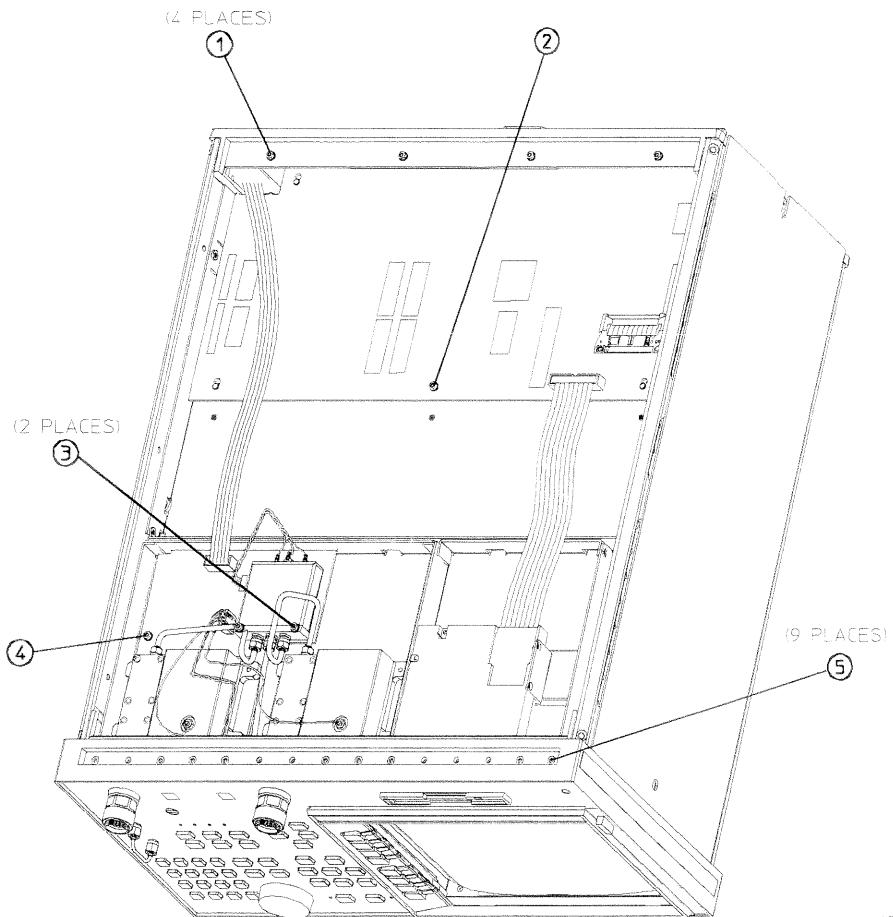
sg684d

Hardware, Bottom

Ref. Desig.	Option	HP Part Number	Qty	Description
1		0515-0458	4	SCREW-MACHINE M3.5×8 CW-PN-TX
2		0515-0430	1	SCREW-MACHINE M3.0×6 CW-PN-TX
3		0515-1410	2	SCREW-MACHINE M3.0×20 CW-PN-TX
4		0515-0430	1	SCREW-MACHINE M3.0×6 CW-PN-TX
5		0515-2086	6	SCREW-MACHINE M4.0×7 PC-FL-TX
6		0515-1400	3	SCREW-MACHINE M3.5×8 PC-FL-TX

13-30 Replaceable Parts

Hardware, Bottom



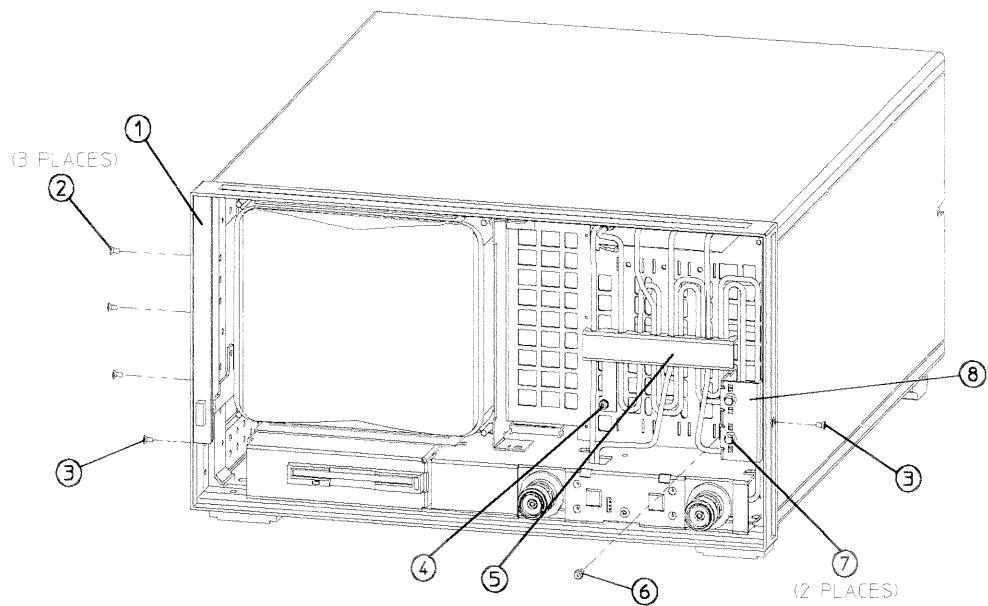
sg685d

Hardware, Front

Ref. Desig.	Option	HP Part Number	Qty	Description
1		08757-40003	1	BEZEL SUPPORT
2		0515-2086	3	SCREW-MACHINE M4.0×7 PC-FL-TX
3		0515-1400	2	SCREW-MACHINE M3.5×8 PC-FL-TX
4		0515-0430	1	SCREW-MACHINE M3.0×6 CW-PN-TX
5		08753-00073	1	BRACKET-CABLE SUPPORT
6		0515-0430	1	SCREW-MACHINE M3.0×6 CW-PN-TX
7		1250-1251	2	ADAPTER-FEMALE SMA/FEMALE SMA
8		08753-00072	1	BRACKET- R CABLE

13-32 Replaceable Parts

Hardware, Front



sg686d

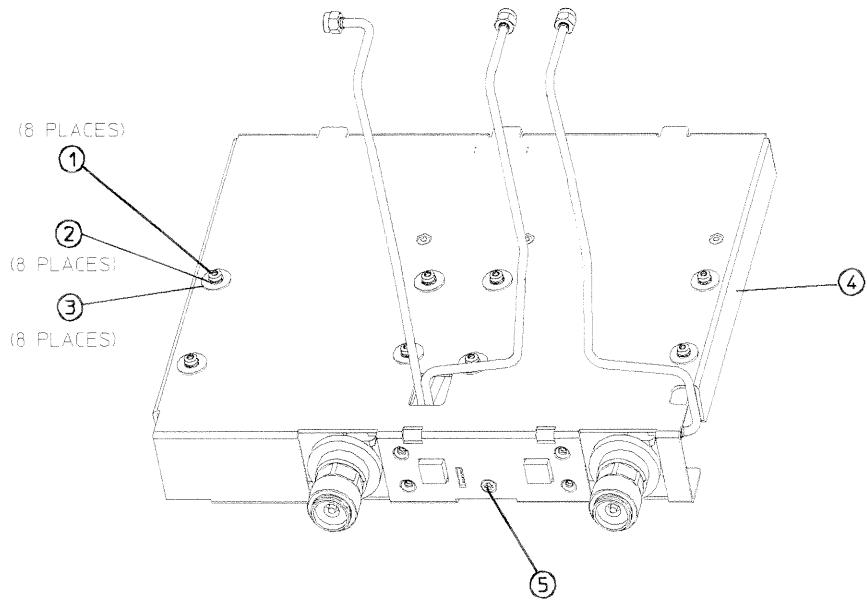
Replaceable Parts 13-33

Hardware, Test Set Deck

Ref. Desig.	Option	HP Part Number	Qty	Description
1		0515-1402	8	SCREW-MACHINE M3.5×8 CW-PN-TX
2		3050-0892	8	WASHER-FLAT M3.8 NOM
3		85047-20022	8	WASHER-SHOULDER
4		08753-00064	1	CHASSIS-TEST SET
5		0515-1946	1	SCREW-MACHINE M3.0×6 PC-FL-TX

13-34 Replaceable Parts

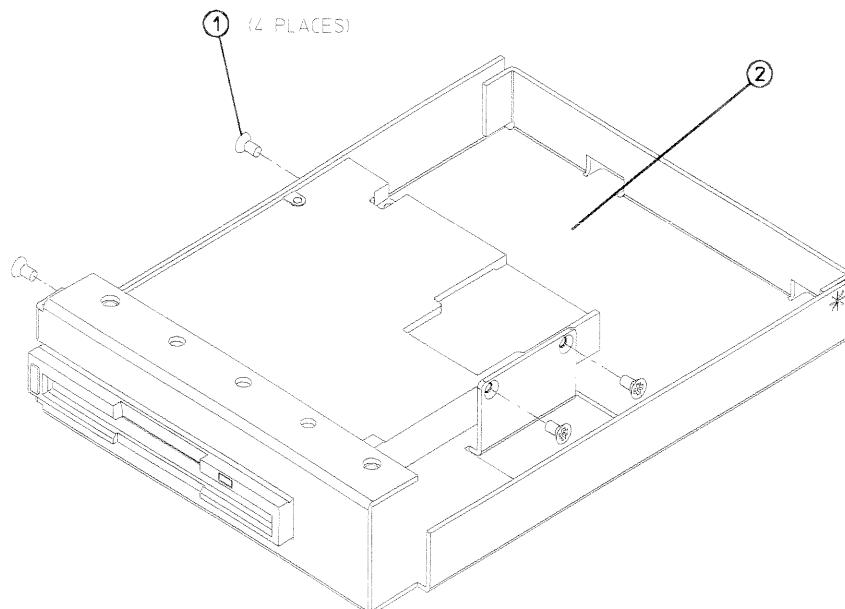
Hardware, Test Set Deck



sg686d

Replaceable Parts 13-35

Hardware, Disk Drive Support

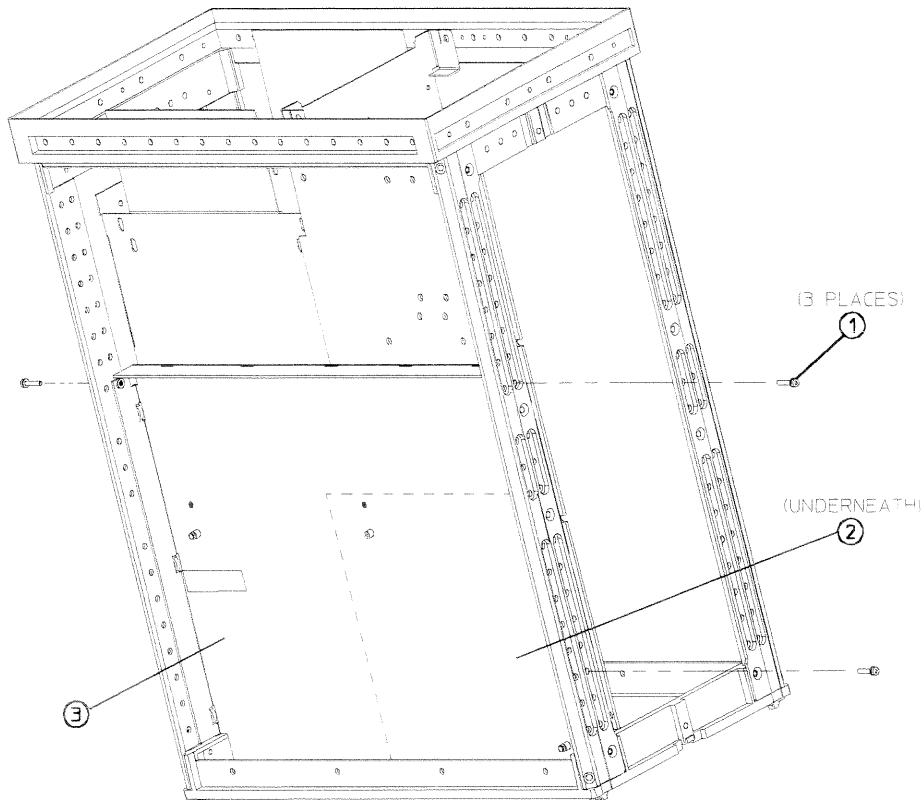


sg687d

Ref. Desig.	Option	HP Part Number	Qty	Description
1		0515-2450	4	SCREW-MACHINE M2.6x4 FL-TX
2		08753-00063	1	DISK SUPPORT

13-36 Replaceable Parts

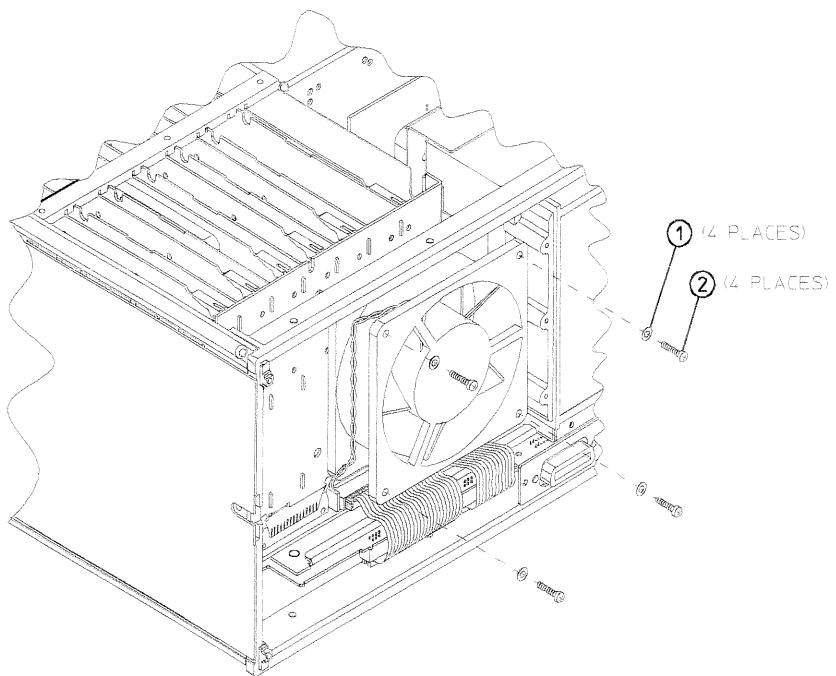
Hardware, Memory Deck



sg689d

Ref. Desig.	Option	HP Part Number	Qty	Description
1		0515-0377	3	SCREW-MACHINE M3.5×10 CW-PN-TX
2		5180-8500	1	INSULATION-MYLAR
3		08753-00067	1	DECK-MEMORY

Hardware, Fan

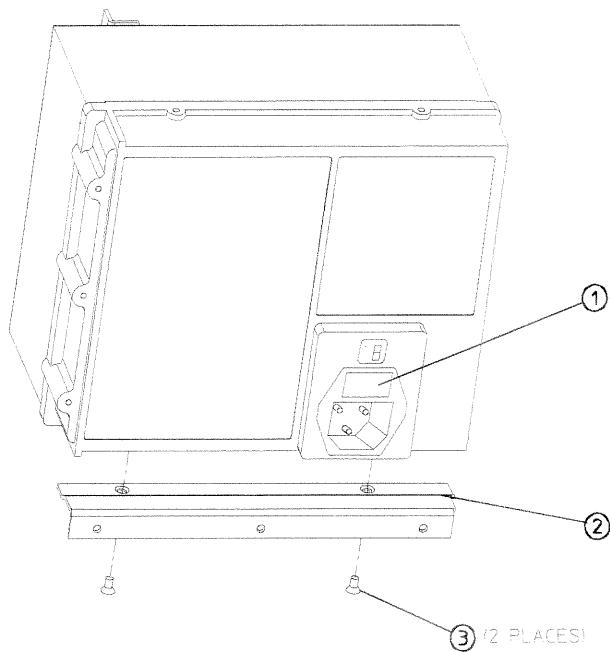


sg690d

Ref. Desig.	Option	HP Part Number	Qty	Description
1		2190-0584	4	WASHER-LOCK M3.0 NOM
2		0515-0965	4	SCREW-MACHINE M3.0×14 SH-HX

13-38 Replaceable Parts

Hardware, Preregulator



sg691d

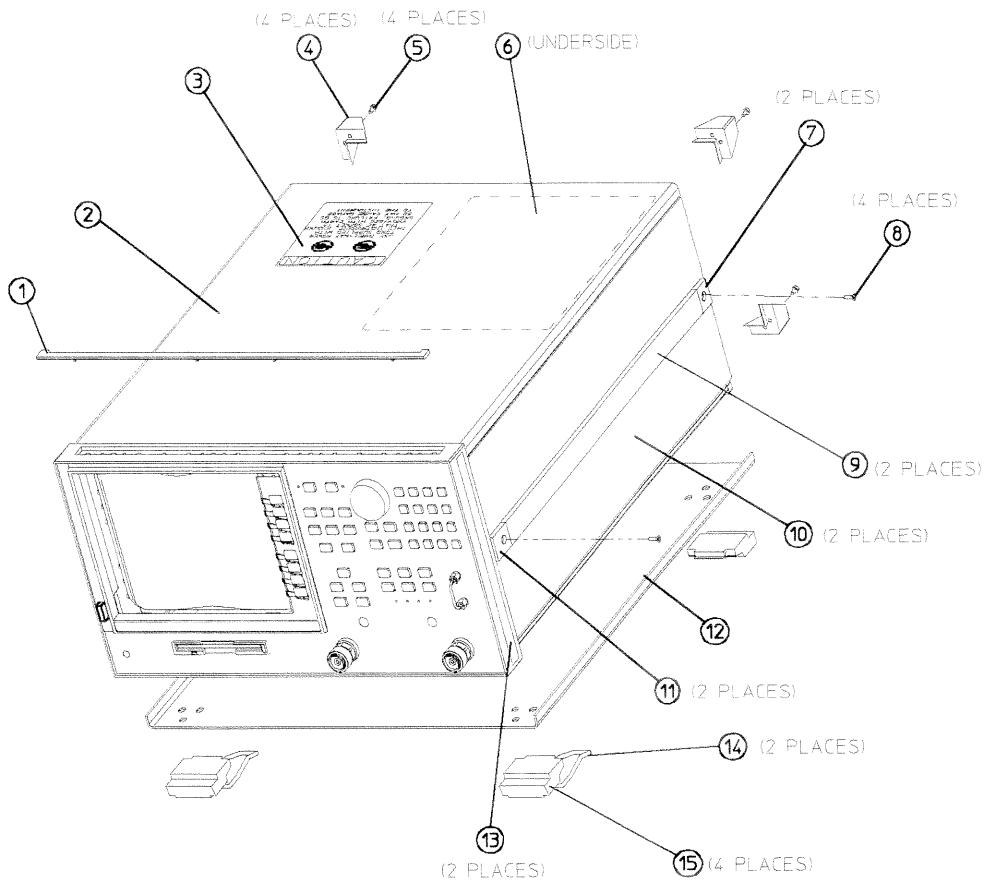
Ref. Desig.	Option	HP Part Number	Qty	Description
1		2110-0780	1	FUSE 3A 250V NON-TIME DELAY
2		08753-00065	1	BRACKET-PREREGULATOR
3		0515-1400	2	SCREW-MACHINE M3.5×8 CW-FL-TX

Chassis Parts, Outside

Ref. Desig.	Option	HP Part Number	Qty	Description
1		5041-8802	1	TRIM STRIP
2		5062-3735	1	COVER TOP
3		08753-80066	1	LABEL-WARNING CAUTION
4		5041-8821	4	REAR STANDOFF
5		0515-1402	4	SCREW-MACHINE M3.5×8 PC-PN-TX
6		08753-80134	1	LABEL-INFORMATION LOCATION DIAGRAM
7		5041-8820	2	STRAP HANDLE CAP-REAR
8		0515-1384	4	SCREW-MACHINE M5.0×10 PC-FL-TX
9		5062-3704	2	STRAP ASSEMBLY
10		5062-3847	2	COVER-SIDE
11		5041-8819	2	STRAP HANDLE CAP-FRONT
12		5062-3747	2	COVER-BOTTOM
13		5001-0541	2	TRIM SIDE
14		1460-1345	2	SPRING-WFR 3.000 LONG
15		5041-8801	4	FOOT-FULL MODULE .5M

13-40 Replaceable Parts

Chassis Parts, Outside



sg692d

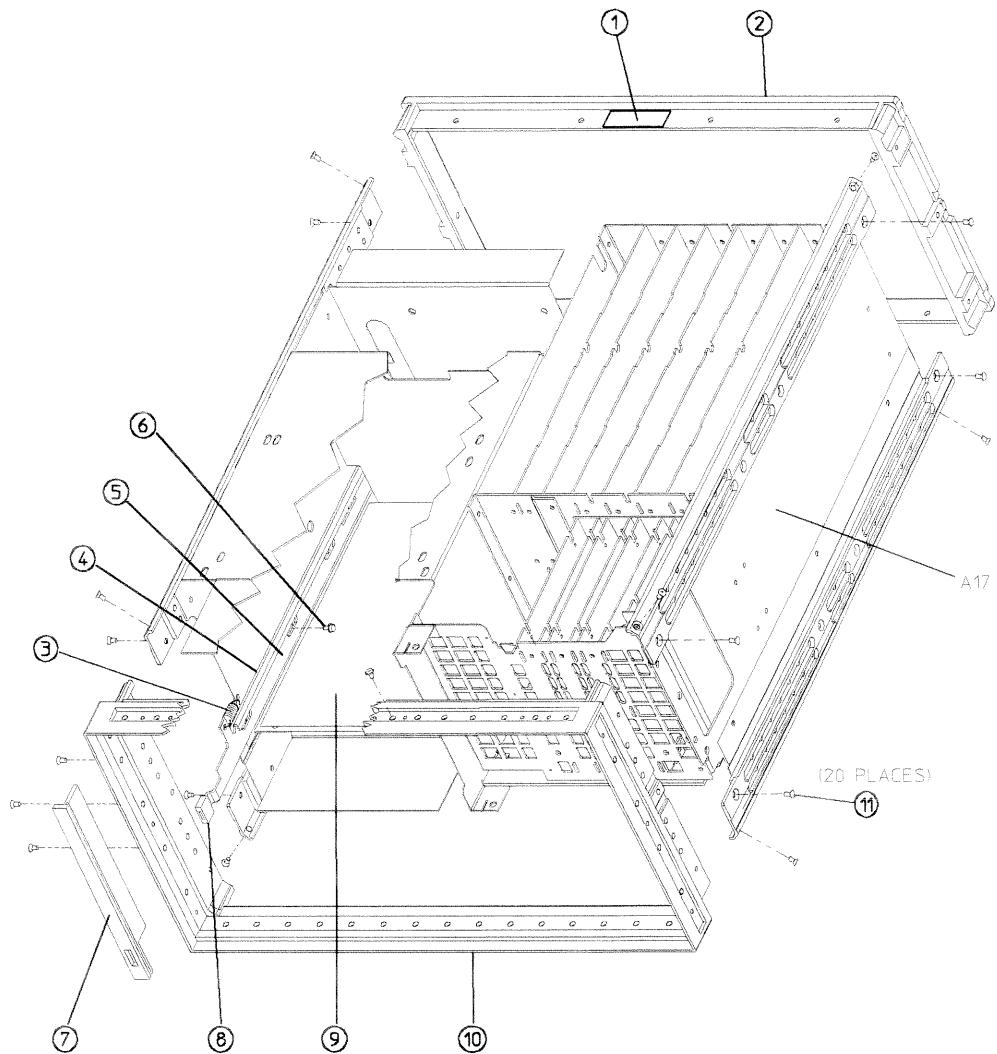
Replaceable Parts 13-41

Chassis Parts, Inside

Ref. Desig.	Option	HP Part Number	Qty	Description
1		7121-2527	1	LABEL-METRIC HARDWARE CAUTION
2		5021-5808	1	REAR FRAME
3		1460-1573	1	SPRING-EXTENSION .138 OD
4		08753-00036	1	INSULATOR-SWITCH
5		08753-00048	1	ACTUATOR-LINE SWITCH
6		0515-0430	1	SCREW-MACHINE M3.0×6 CW-PN-TX
7		08757-40003	1	BEZEL SUPPORT
8		08757-40005	1	LINE BUTTON
9		5180-8500	1	INSULATOR-MYLAR
10		5021-8407	1	FRONT FRAME
11		0515-2086	20	SCREW-MACHINE M4.0×7 PC-FL-TX
A17		08753-60181	1	REPL KIT-MOTHERBOARD (includes card cage & struts)

13-42 Replaceable Parts

Chassis Parts, Inside



sg693d

Replaceable Parts 13-43

Miscellaneous

Description	HP Part Number
Service Tools	
HP 8753 TOOL KIT <i>includes the following:</i>	
RF CABLE-INPUT R	08753-20028
EXTENDER BOARD ASSEMBLY-RECEIVER	08753-60019
EXTENDER BOARD ASSEMBLY-SOURCE	08753-60020
EXTENDER BOARD ASSEMBLY-CARD CAGE	08753-60155
ADAPTER-MALE SMB TO MALE SMB	1250-0669
ADAPTER-MALE TYPE N TO FEMALE SMA	1250-1250
CABLE ASSEMBLY	5061-1022
BAG-ANTISTATIC 13×15	9222-1132
Documentation	
HP 8753D SERVICE GUIDE (includes Option 011)	08753-90261
HP 8753D MANUAL SET <i>includes the following:</i>	
HP 8753D EXAMPLE PROGRAM DISK #1	08753-10028
HP 8753D EXAMPLE PROGRAM DISK #2	08753-10029
HP 8753D PROGRAMMING GUIDE	08753-90256
HP 8753D USER'S GUIDE (<i>includes Quick Reference, 08753-90259</i>)	08753-90257
HP 8753D INSTALLATION/QUICK START GUIDE	08753-90258
HP 8753D SYSTEM VERIFICATION AND PERFORMANCE TESTS	08753-90308
HP 8753D OPTION 011 MANUAL SET <i>includes the following:</i>	
HP 8753D EXAMPLE PROGRAM DISK #1	08753-10028
HP 8753D EXAMPLE PROGRAM DISK #2	08753-10029
HP 8753D PROGRAMMING GUIDE	08753-90256
HP 8753D OPTION 011 USER'S GUIDE (<i>includes Quick Reference, 08753-90305</i>)	08753-90304
HP 8753D OPTION 011 INSTALLATION/QUICK START GUIDE	08753-90303
HP 8753D OPTION 011 SYSTEM VERIFICATION AND PERFORMANCE TESTS	08753-90314
Upgrade Kits	
HARMONIC MEASUREMENT UPGRADE KIT	HP 11883A
6 GHz UPGRADE KIT FOR HP 8753D	HP 11884B
6 GHz UPGRADE KIT FOR HP 8753D OPTION 011	HP 11884C
TIME DOMAIN UPGRADE KIT	HP 85019B
FIRMWARE UPGRADE KIT	08753-60185
HIGH-STABILITY FREQUENCY REFERENCE RETROFIT KIT	08753-60236

13-44 Replaceable Parts

Miscellaneous

Description	HP Part Number
Protective Caps for Connectors	
FEMALE HP-IB CONNECTOR	1252-5007
FEMALE TEST SET I/O	1252-4690
FEMALE PARALLEL PORT	1252-4690
RS-232 CONNECTOR	1252-4697
7-mm TEST PORTS	1401-0249
FEMALE TYPE-N TEST PORTS (OPTION 011)	1401-0247
Fuses used on the A8 Post Regulator	
FUSE 0.5A 125V NON-TIME DELAY 0.25×0.27	2110-0046
FUSE 0.75A 125V NON-TIME DELAY 0.25×0.27	2110-0424
FUSE 1A 125V NON-TIME DELAY 0.25×0.27	2110-0047
FUSE 2A 125V NON-TIME DELAY 0.25×0.27	2110-0425
FUSE 4A 125V NON-TIME DELAY 0.25×0.27	2110-0476
HP-IB Cables	
HP-IB CABLE, 1M (3.3 FT)	HP 10833A
HP-IB CABLE, 2M (6.6 FT)	HP 10833B
HP-IB CABLE, 4M (13.2 FT)	HP 10833C
HP-IB CABLE, 0.5M (1.6 FT)	HP 10833D
Touch-up Paint	
DOVE GRAY <i>for use on frame around front panel and painted portion of handles</i>	6010-1146
FRENCH GRAY <i>for use on side, top, and bottom covers</i>	6010-1147
PARCHMENT WHITE <i>for use on rack mount flanges, rack support flanges, and front panels</i>	6010-1148
ESD Supplies	
ADJUSTABLE ANTISTATIC WRIST STRAP	9300-1367
5 FT GROUNDING CORD <i>for wrist strap</i>	9300-0980
2 × 4 FT ANTISTATIC TABLE MAT WITH 15 FT GROUND WIRE	9300-0797
ANTISTATIC HEEL STRAP <i>for use on conductive floors</i>	9300-1126
Other	
HP 8753D KEYBOARD OVERLAY <i>for external keyboard</i>	08753-80131
RACK MOUNT KIT WITHOUT HANDLES	5062-3979
RACK MOUNT KIT WITH HANDLES	5062-4073
FRONT HANDLE	5062-3991
FLOPPY DISKS, 3.5 INCH DOUBLE-SIDED (box of 10)	HP 92192A

Table 13-1.
Reference Designations, Abbreviations, and Options

REFERENCE DESIGNATIONS	
A	assembly
B	fan; motor
J	electrical connector (stationary portion); jack
RPG	rotary pulse generator
W	cable; transmission path; wire

ABBREVIATIONS	
A	ampere
ALC	automatic level control
ASSY	assembly
AUX	auxiliary
BD	board
COAX	coaxial
CPU	central processing unit
CW	conical washer (screws)
D	diameter
ESD	electrostatic discharge
EXT	external
EYO	YIG oscillator
FL	flathead (screws)
FP	front panel
FRAC-N	fractional N
FREQ	frequency
GHz	gigahertz
HEX	hexagonal
HP	Hewlett-Packard
HP-IB	Hewlett-Packard interface bus
HX	hex recess (screws)
ID	inside diameter
IF	intermediate frequency
I/O	input/output
LED	light-emitting diode

OPTIONS	
002	harmonics measurement
006	6 GHz performance
010	time domain
011	w/o test set
075	75 ohm test set
1D5	10 MHz precision ref

14

Assembly Replacement and Post-Repair Procedures

This chapter contains procedures for removing and replacing the major assemblies of the HP 8753D network analyzer. A table showing the corresponding post-repair procedures for each replaced assembly is located at the end of this chapter.

Replacing an assembly

The following steps show the sequence to replace an assembly in an HP 8753D Network Analyzer.

1. Identify the faulty group. Refer to Chapter 4, "Start Troubleshooting Here." Follow up with the appropriate troubleshooting chapter that identifies the faulty assembly.
2. Order a replacement assembly. Refer to Chapter 13, "Replaceable Parts."
3. Replace the faulty assembly and determine what adjustments are necessary. Refer to Chapter 14, "Assembly Replacement and Post-Repair Procedures."
4. Perform the necessary adjustments. Refer to Chapter 3, "Adjustments and Correction Constants."
5. Perform the necessary performance tests. Refer to Chapter 2, "System Verification and Performance Tests."

Warning **These servicing instructions are for use by qualified personnel only. To avoid electrical shock, do not perform any servicing unless you are qualified to do so.**

Warning **The opening of covers or removal of parts is likely to expose dangerous voltages. Disconnect the instrument from all voltage sources while it is being opened.**

Warning **The power cord is connected to internal capacitors that may remain live for 10 seconds after disconnecting the plug from its power supply.**

Caution Many of the assemblies in this instrument are very susceptible to damage from ESD (electrostatic discharge). Perform the following procedures only at a static-safe workstation and wear a grounding strap.

Procedures described in this chapter

The following pages describe assembly replacement procedures for the HP 8753D assemblies listed below:

- Line Fuse
- Covers
- Front Panel Assembly
- Rear Panel Assembly
- Test Set Deck
- **A1** Keyboard
- **A2** Front Panel Interface
- **A3** Source Assembly
- **A4, A5, A6** Samplers and **A7** Pulse Generator
- **A8, A10, A11, A12, A13, A14** Card Cage Boards
- **A9** CPU Board
- **A9BT1** Battery
- **A15** Preregulator
- **A16** Rear Panel Interface
- **A17** Motherboard Assembly
- **A18** Display
- **A19** Graphics Processor
- **A20** Disk Drive
- **A21, A22** Test Port Couplers
- **A23** LED Board
- **A24** Transfer Switch
- **A25** Test Set Interface
- **A26** High Stability Frequency Reference (Option 1D5)
- **B1** Fan

Line Fuse

Tools Required

- small slot screwdriver

Removal

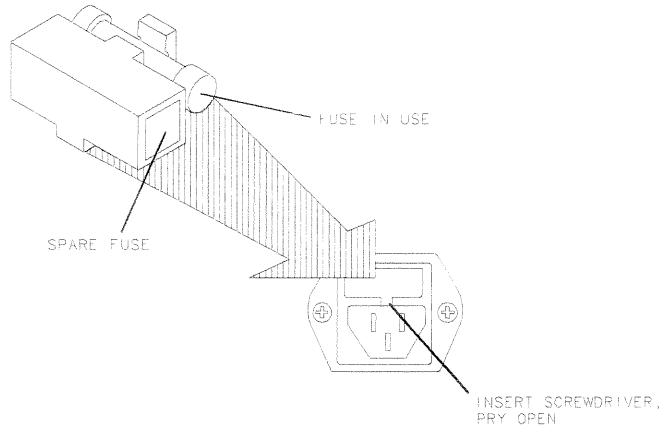
Warning	For continued protection against fire hazard, replace fuse only with same type and rating (3 A 250 V F). The use of other fuses or materials is prohibited.
----------------	--

1. Disconnect the power cord.
2. Use a small slot screwdriver to pry open the fuse holder.
3. Replace the blown fuse with a 3 A 250 V F fuse (HP part number 2110-0708).

Replacement

1. Simply replace the fuse holder.

Line Fuse



qq652d

Covers

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- T-20 TORX screwdriver

Removing the top cover

1. Remove both upper rear feet (item 1) by loosening the attaching screws (item 2).
2. Loosen the top cover screw (item 3).
3. Slide cover off.

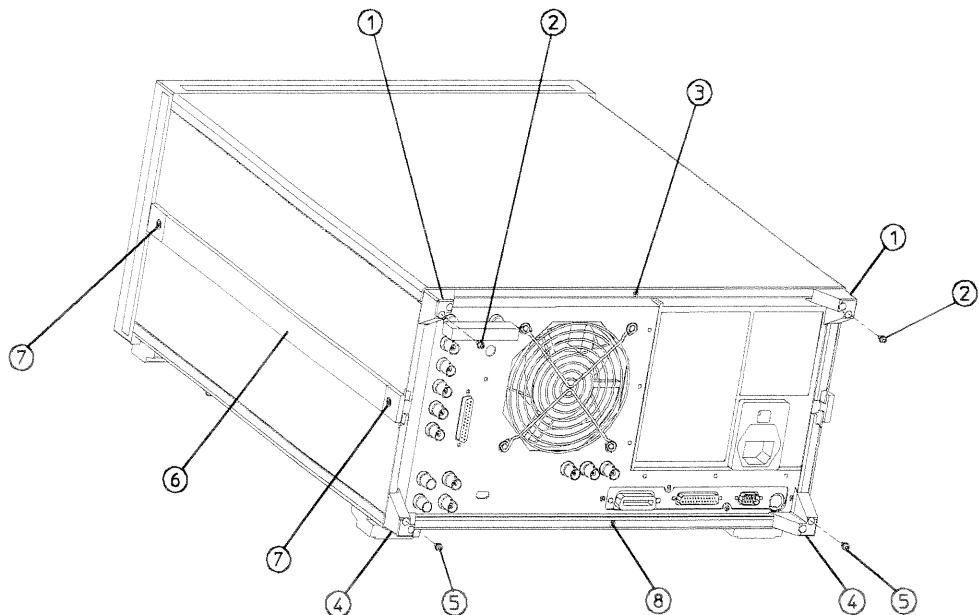
Removing the side covers

1. Remove the top cover.
2. Remove the lower rear foot (item 4) that corresponds to the side cover you want to remove by loosening the attaching screw (item 5).
3. Remove the handle assembly (item 6) by loosening the attaching screws (item 7).
4. Slide cover off.

Removing the bottom cover

1. Remove both lower rear feet (item 4) by loosening the attaching screws (item 5).
2. Loosen the bottom cover screw (item 8).
3. Slide cover off.

Covers



sg695d

Front Panel Assembly

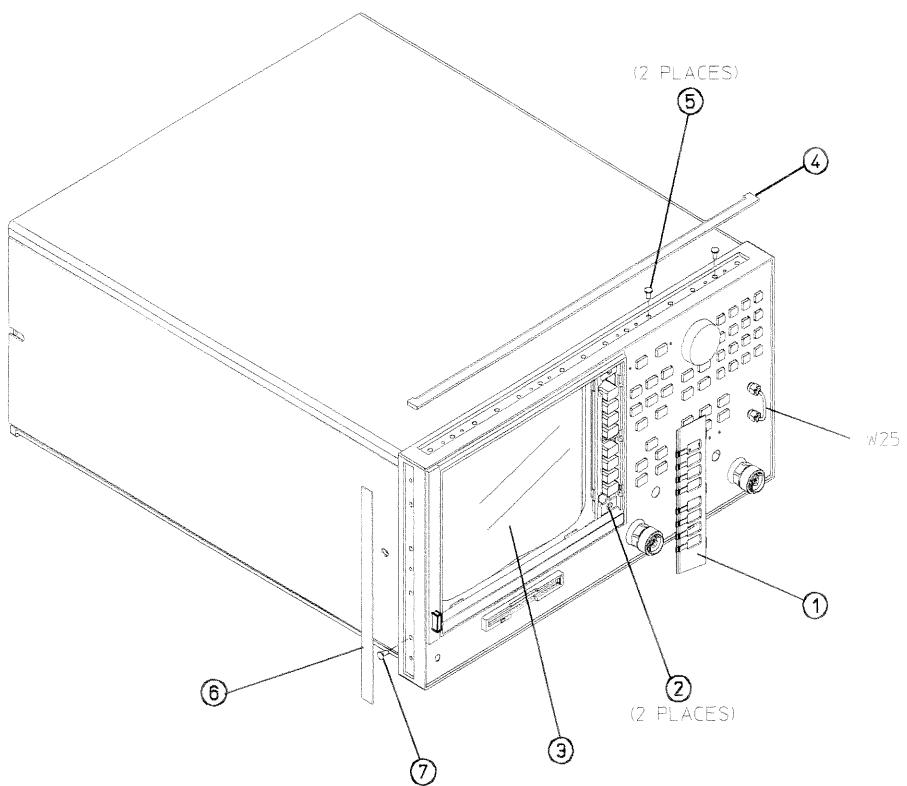
Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- small slot screwdriver
- ESD (electrostatic discharge) grounding wrist strap
- 5/16-inch open-end torque wrench (set to 10 in-lb)

Removal

1. Disconnect the power cord.
2. Remove the bezel's softkey cover (item 1) by sliding your fingernail under the left edge, near the top or bottom of the cover. Pry the softkey cover away from the bezel. If you use another tool, take care not to scratch the glass.
3. Remove the two screws (item 2) exposed by the previous step. The bezel (item 3) is now free from the frame. Remove it.
4. Remove the semi-rigid R-channel cable (W25) from the front panel.
5. Remove the trim strip (item 4) from the top edge of the front frame by prying under the strip with a small slot screwdriver.
6. Remove the two screws (item 5) from the top edge of the frame.
7. Remove the left-side trim strip (item 6) from the front frame to expose four screws. Remove the bottom screw (item 7).

Front Panel Assembly



sg650d

Front Panel Assembly

8. Remove the left front foot (item 8).
9. Remove the three screws (item 9) from the bottom edge of the frame.
10. Slide the front panel over the test port connectors (item 10). The test port connectors have some side-to-side play in them that allows them to be moved slightly to better fit the front panel openings as the front panel is installed.
11. Disconnect the ribbon cable (W17) from the front panel by pressing down and out on the connector locks. The front panel is now free from the instrument.

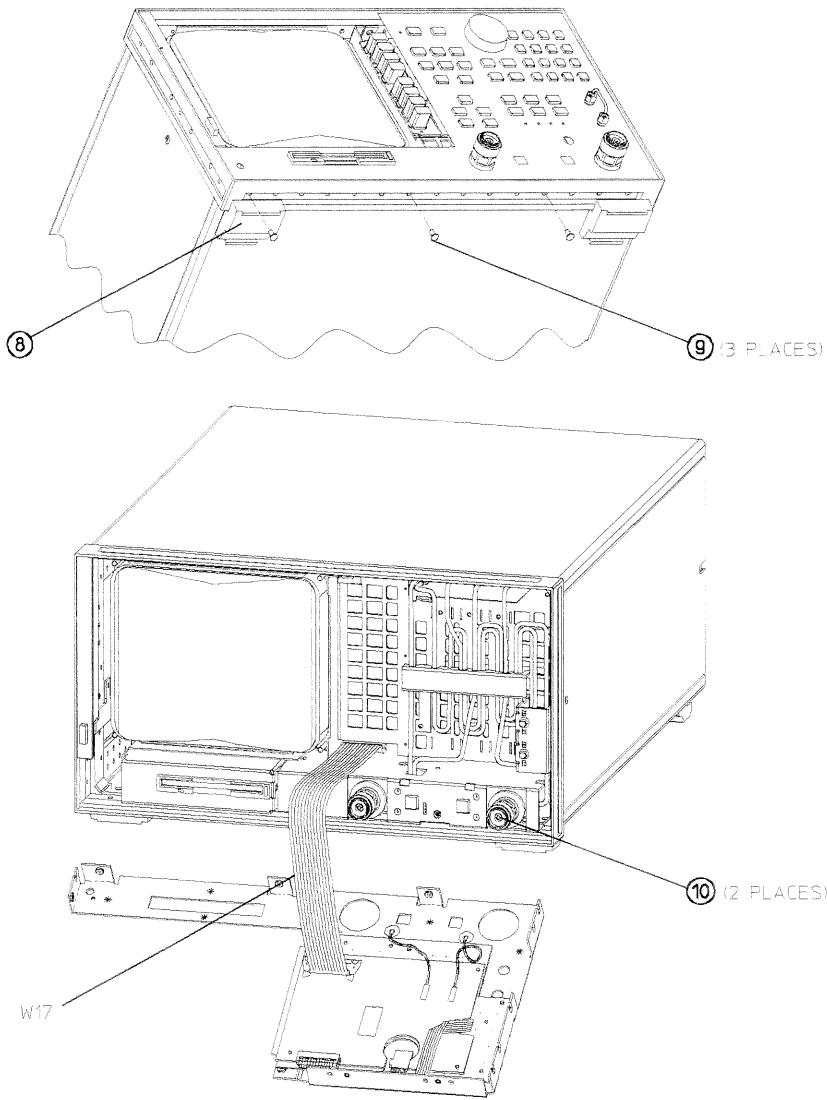
Replacement

1. Reverse the order of the removal procedure.

Note

When reconnecting semi-rigid cables, it is recommended that the connections be torqued to 10 in-lb.

Front Panel Assembly



sg651d

Rear Panel Assembly

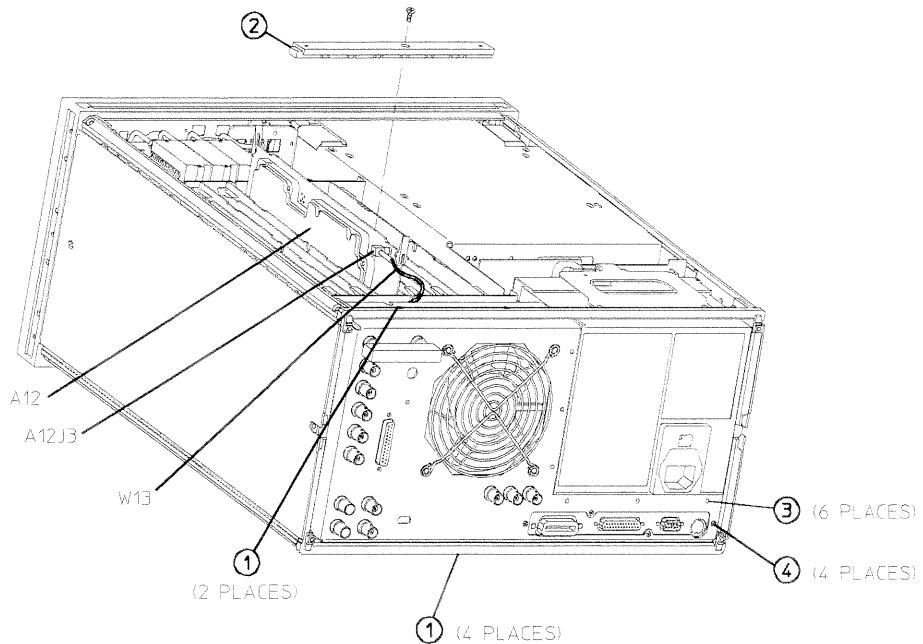
Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap

Removal

1. Disconnect the power cord and remove the top and bottom covers (refer to "Covers" in this chapter).
2. Remove six screws (item 1) from the rear frame: two from the top edge and four from the bottom edge.
3. Remove the screw from the pc board stabilizer (item 2) and remove the stabilizer.
4. Lift the reference board (A12) from its motherboard connector and disconnect W13 from A12J3.
5. Remove the six screws (item 3), next to the preregulator, from the rear panel as shown.
6. Remove the four screws (item 4), surrounding the connector interfaces, from the rear panel as shown.

Rear Panel Assembly



sg658d

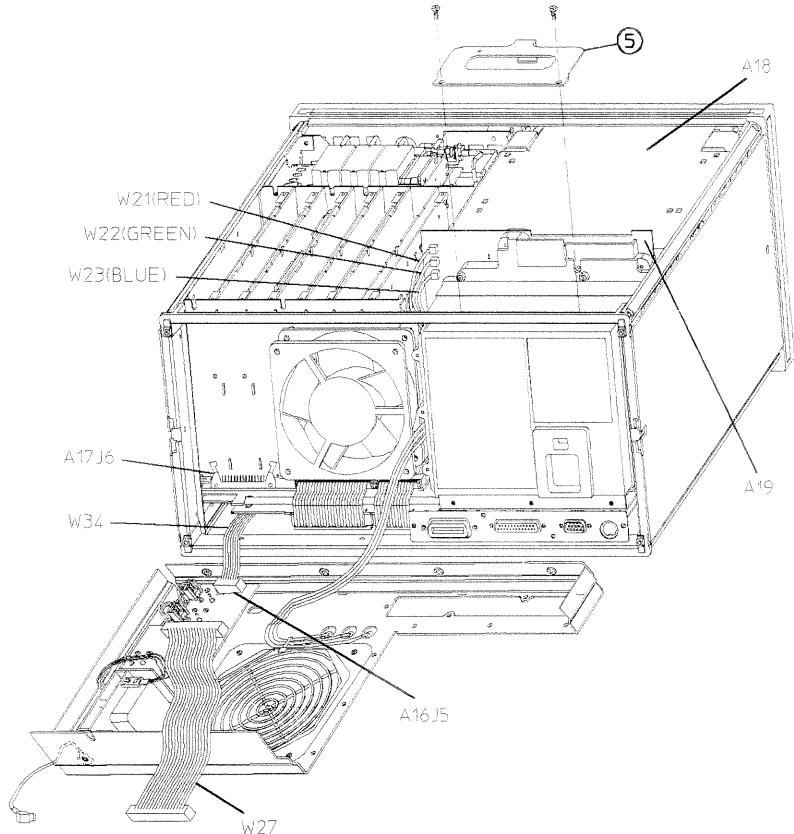
Rear Panel Assembly

7. Pull the rear panel away from the frame. Disconnect the ribbon cable (W27) from the motherboard connector (A17J6), pressing down and out on the connector locks. Disconnect the smaller ribbon cable (W34) from the rear panel interface board (A16J5). The rear panel is now connected only by three flexible cables (W21, W22, and W23).
8. Remove the bracket (item 5) that secures the graphics board (A19), removing the two screws that attach it to the rear frame. *The preregulator is now sitting loosely in the instrument.* Gently press the top of the graphics board (A19) towards the display (A18) then lift up. Disconnect the three flexible cables (W21, W22, and W23) from the graphics board (A19). The rear panel is now detached.

Replacement

1. Reverse the order of the removal procedure.

Rear Panel Assembly



sg659d

Test Set Deck

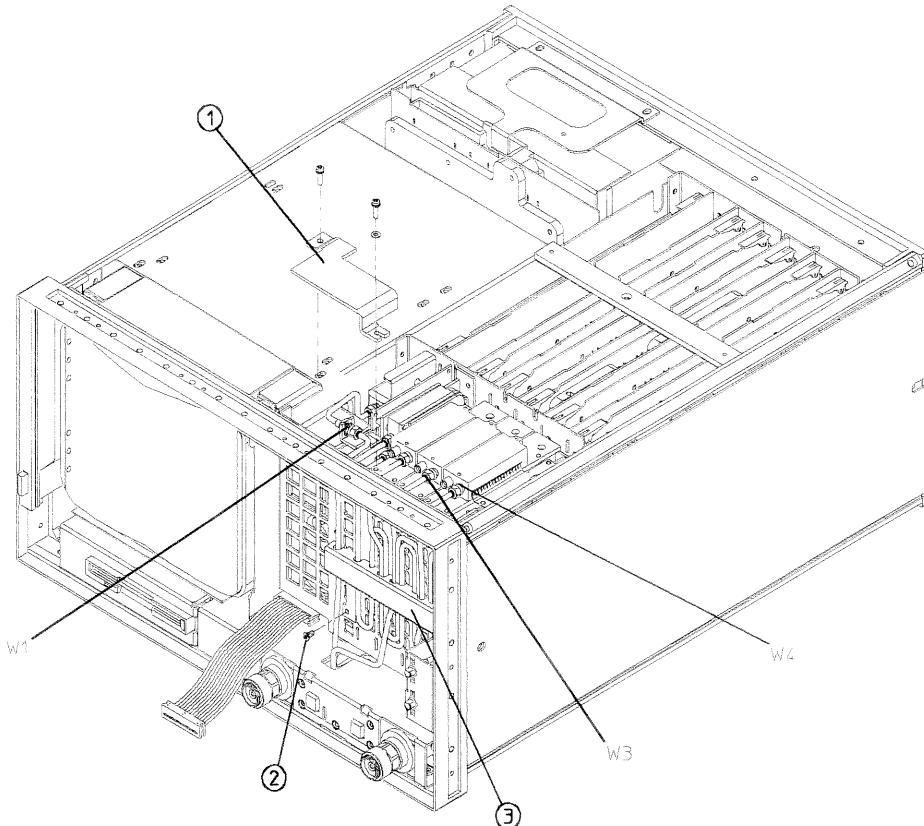
Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- small slot screwdriver
- ESD (electrostatic discharge) grounding wrist strap
- 5/16-inch open-end torque wrench (set to 10 in-lb)

Removal

1. Disconnect the power cord and remove the top and bottom covers (refer to “Covers” in this chapter).
2. Remove the front panel (refer to “Front Panel Assembly” in this chapter).
3. Remove the source bracket (item 1).
4. Disconnect the semi-rigid cables (W1, W3, and W4) from the source and the samplers.
5. Remove the screw (item 2) that secures the bracket (item 3) holding the semi-rigid cables against the card cage assembly. Remove the bracket.

Test Set Deck



sg665d

Test Set Deck

6. Turn the instrument upside-down and disconnect W34 from A25J1 on the test set interface board.
7. Remove the four screws (item 4) from the bottom edge of the front frame that secure the test set deck (item 5).
8. Carefully slide the test set deck out of the instrument.

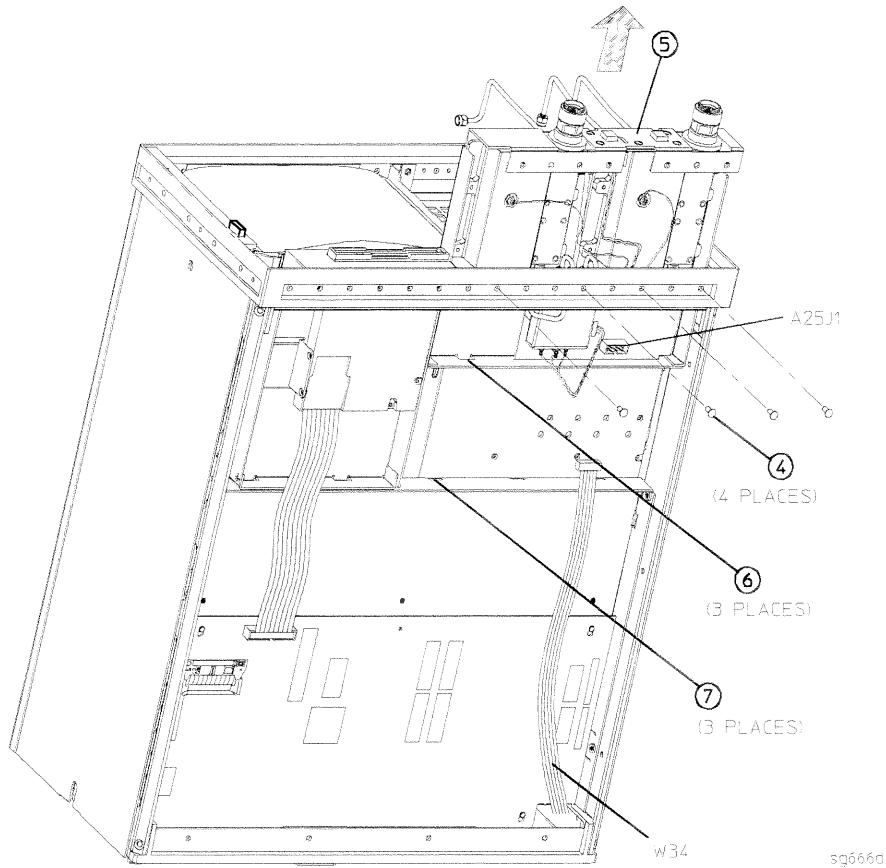
Replacement

1. Reverse the order of the removal procedure.

Note

- When replacing the test set deck, ensure that the three tabs (item 4) at the rear of the deck slide into the slots (item 5) of the CPU board deck.
 - When reconnecting semi-rigid cables, it is recommended that the connections be torqued to 10 in-lb.
-

Test Set Deck



A1 Keyboard

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- small slot screwdriver
- ESD (electrostatic discharge) grounding wrist strap
- 5/16-inch open-end torque wrench (set to 10 in-lb)

Removal

1. Remove the front panel interface board (refer to “A2 Front Panel Interface” in this chapter).
2. Remove the eight screws (item 2) that attach the front panel keyboard assembly (A1) to the front panel. Detach the keyboard assembly.

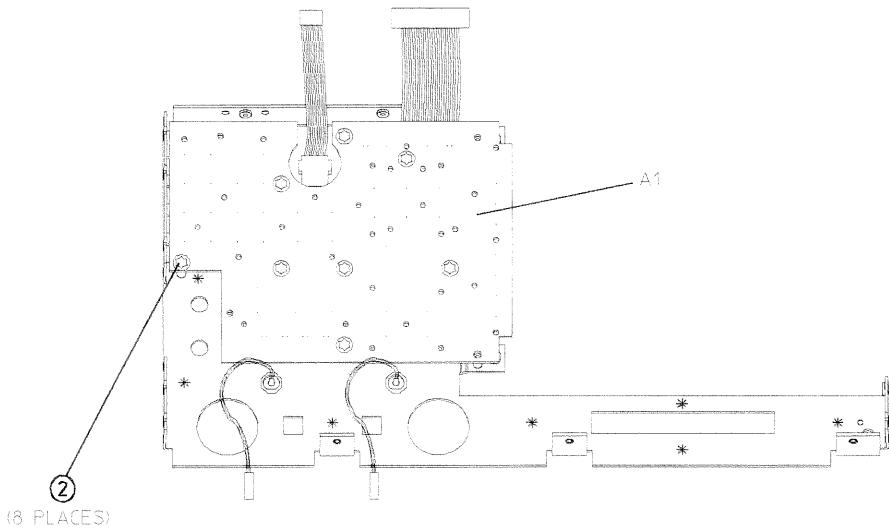
Replacement

1. Reverse the order of the removal procedure.

Note When reinstalling the keyboard assembly (A1), place the eight screws in the holes plated with a circular pattern. (The other four holes secure the interface board (A2).)

Initially, you should install all eight screws loosely. Then you can go back and tighten each one. This will ensure that the board is correctly aligned.

A1 Keyboard



sg653d

A2 Front Panel Interface

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- small slot screwdriver
- ESD (electrostatic discharge) grounding wrist strap
- 5/16-inch open-end torque wrench (set to 10 in-lb)

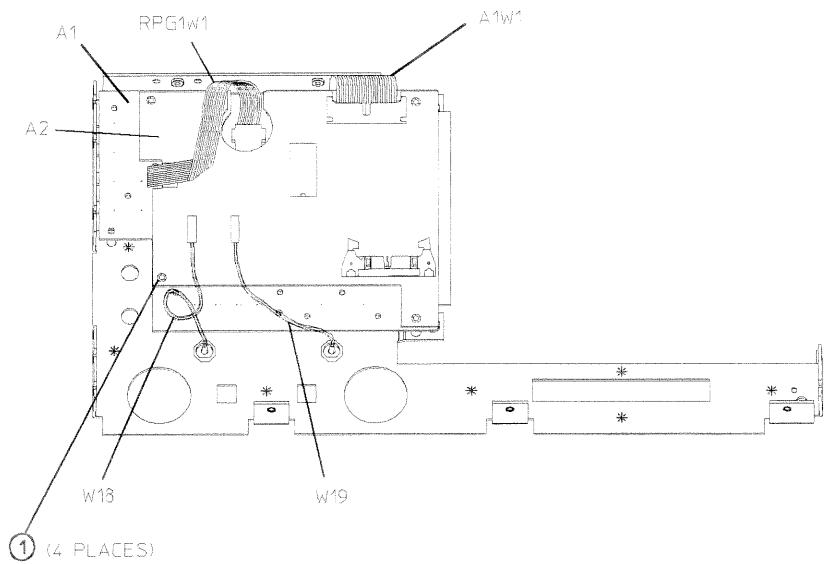
Removal

1. Remove the front panel (refer to “Front Panel Assembly” in this chapter).
2. Disconnect W18, W19, and RPG1W1 from the interface board (A2).
3. Disconnect A1W1 from the interface board (A2), inserting the blade of a small slot screwdriver into the slots on the sides of the ribbon cable connector. Gently pry upward on either side of the connector until the ribbon cable is detached.
4. Remove the four screws (item 1) from the corners of the interface board (A2). Remove the board.

Replacement

1. Reverse the order of the removal procedure.

A2 Front Panel Interface



sg652d

A3 Source Assembly

Tools Required

- T-15 TORX screwdriver
- 5/16-inch open-end torque wrench (set to 10 in-lb)
- ESD (electrostatic discharge) grounding wrist strap

Removal

1. Disconnect the power cord and remove the top cover (refer to “Covers” in this chapter).
2. Remove the source bracket (item 1).
3. Disconnect the two semi-rigid cables (W1 and W24) and one flexible cable (W26) from the source assembly (A3).
4. Lift the two retention clips (item 2) at the front and rear of the source assembly (A3) to an upright position.
5. The source is seated in a motherboard edge connector. Hold the two loose semi-rigid cables (W1 and W24) to the right and lift up on the source bracket handle (item 3) to remove the source assembly from the instrument.

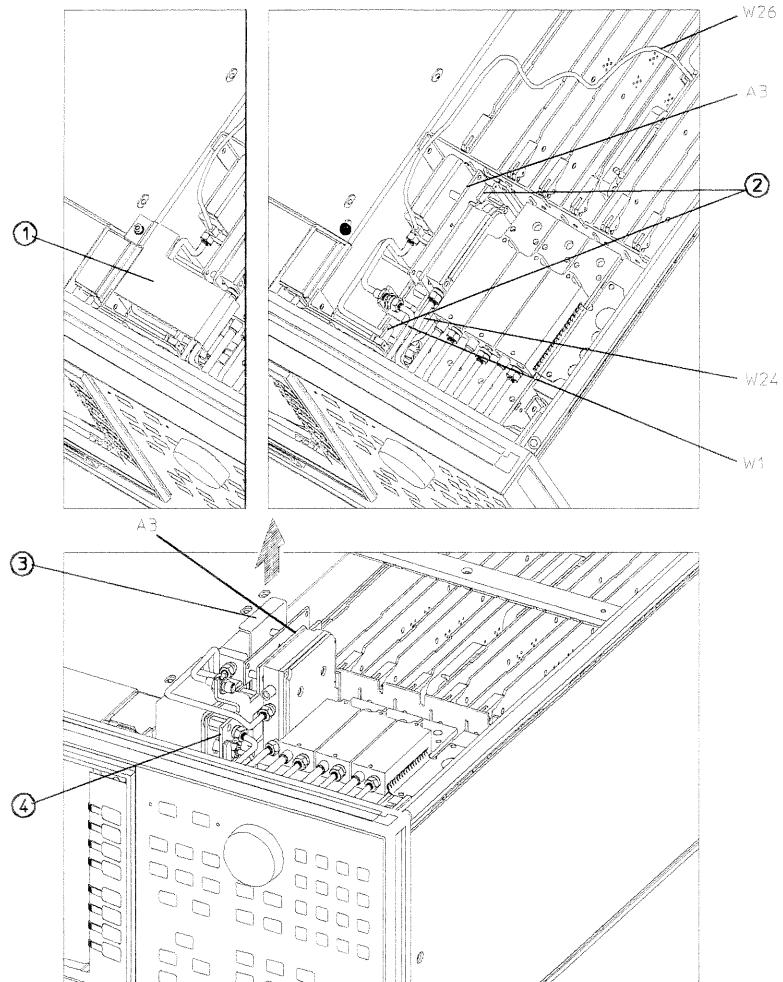
Replacement

1. Slide the edges of the sheet metal partition (item 4) into the guides at the front and back of the source compartment. Press down on the module to ensure that it is well seated in the motherboard connector.
2. Push down the retention clips. Reconnect the two semi-rigid cables (W1 and W24) and one flexible cable (W26) to the source assembly.

Note

When reconnecting semi-rigid cables, it is recommended that the connections be torqued to 10 in-lb.

A3 Source Assembly



sg654d

A4, A5, A6 Samplers and A7 Pulse Generator

Tools Required

- T-10 TORX screwdriver
- 5/16-inch open-end torque wrench (set to 10 in-lb)
- ESD (electrostatic discharge) grounding wrist strap

Removal

1. Disconnect the power cord and remove the top cover (refer to "Covers" in this chapter).
2. To remove the R sampler (A4), you must remove the source bracket (item 1).
3. Disconnect all cables from the top of the sampler (A4/A5/A6) or pulse generator (A7).
4. Remove the screws from the top of the assembly. Extract the assembly from the slot.

Note

- If you are removing the pulse generator (A7), the grounding clip, which rests on top of the assembly, will become loose once the four screws are removed. Be sure to replace the grounding clip when reinstalling the pulse generator assembly.
 - If you're removing more than one sampler, be careful not to mix them. The R sampler (A4) is different from the A and B samplers (A5 and A6).
-

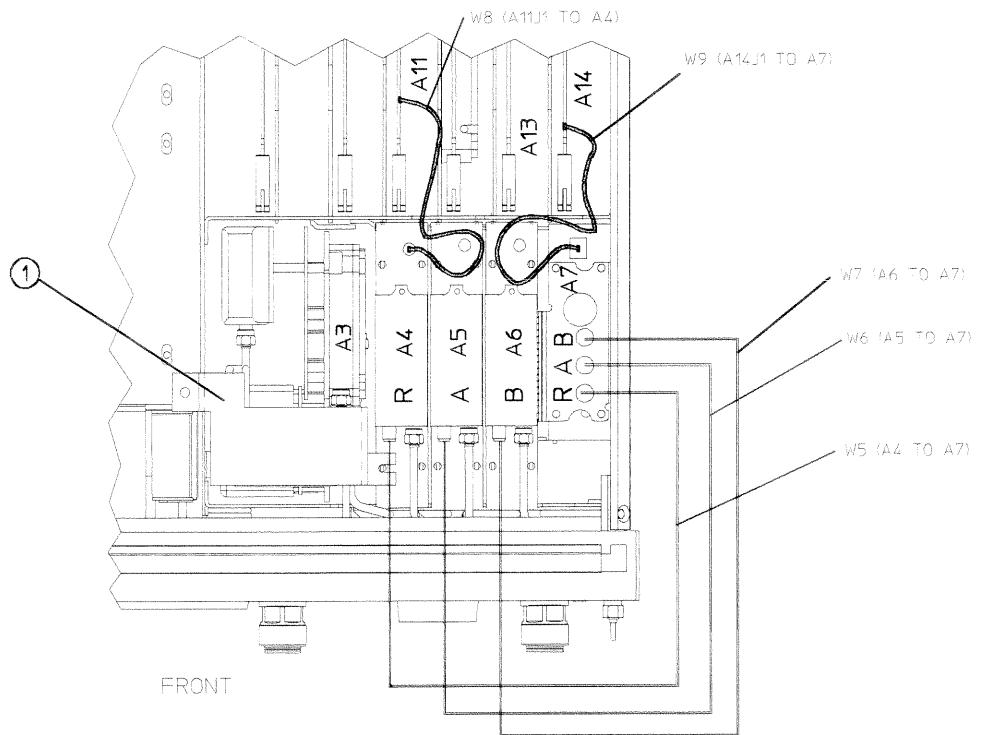
Replacement

1. Reverse the order of the removal procedure.

Note

- When reconnecting semi-rigid cables, it is recommended that the connections be torqued to 10 in-lb.
 - Be sure to route W8 and W9 as shown. No excess wire should be hanging in the A11 and A14 board slots. Routing the wires in this manner will reduce noise and crosstalk.
-

A4, A5, A6 Samplers and A7 Pulse Generator



sg655d

A8, A10, A11, A12, A13, A14 Card Cage Boards

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap

Removal

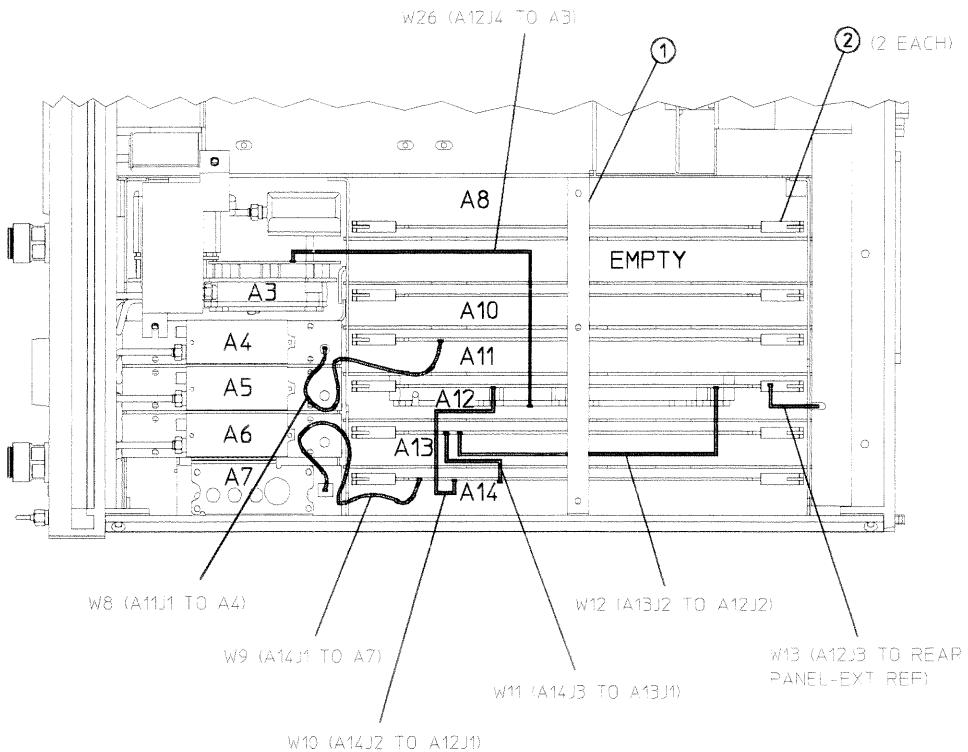
1. Disconnect the power cord and remove the top cover (refer to "Covers" in this chapter).
2. Remove the screw from the pc board stabilizer (item 1) and remove the stabilizer.
3. Lift the two extractors (item 2) located at each end of the board. Lift the board from the card cage slot, just enough to disconnect any flexible cables that may be connected to it.
4. Remove the board from the card cage slot.

Replacement

1. Reverse the order of the removal procedure.

Note Be sure to route W8 and W9 as shown. No excess wire should be hanging in the A11 and A14 board slots. Routing the wires in this manner will reduce noise and crosstalk in the instrument.

A8, A10, A11, A12, A13, A14 Card Cage Boards



sg656d

A9 CPU Board

Tools Required

- T-10 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap

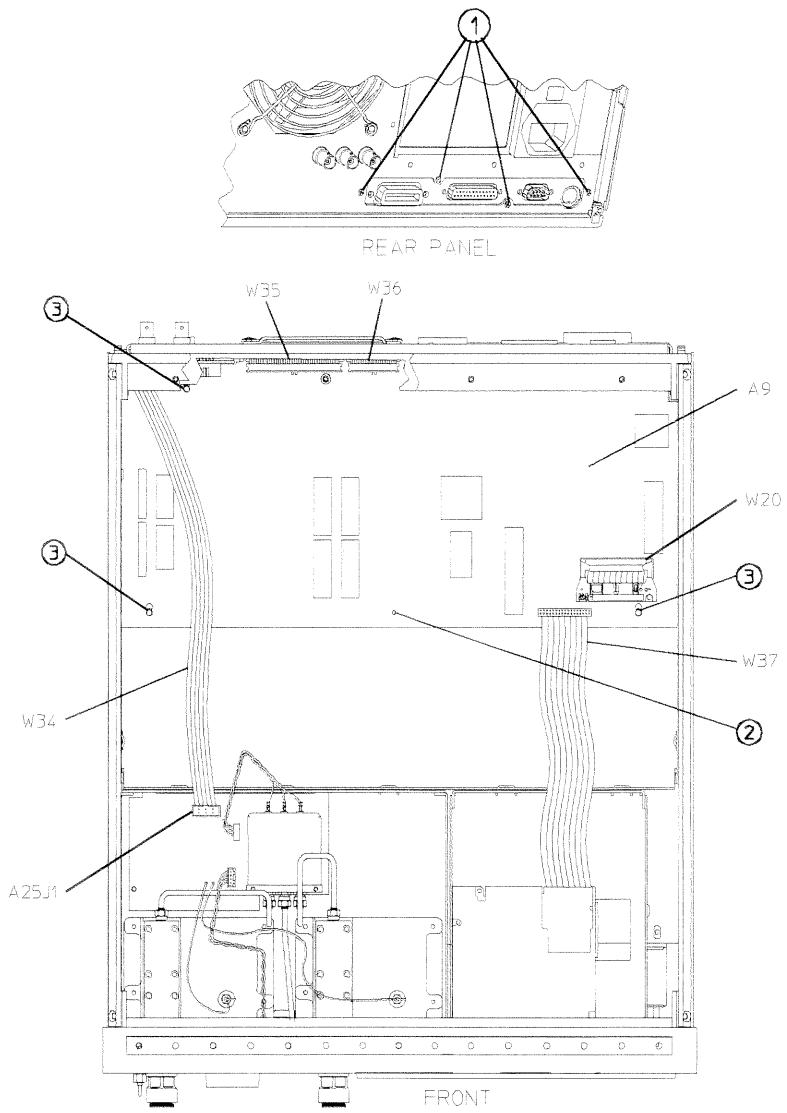
Removal

1. Disconnect the power cord.
2. Remove the four screws (item 1) on the rear panel.
3. Remove the bottom cover (refer to “Covers” in this chapter).
4. Remove the screw (item 2) that secures the CPU board (A9) to the deck.
Slide the board towards the front of the instrument so that it disconnects from the three standoffs (item 3).
5. Disconnect the four ribbon cables (W20, W35, W36, and W37) from the CPU board (A9).
6. Disconnect W34 from A25J1.
7. Lift the board off of the standoffs.

Replacement

1. Reverse the order of the removal procedure.

A9 CPU Board



sg657d

A9BT1 Battery

Tools Required

- T-10 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap
- soldering iron with associated soldering tools

Removal

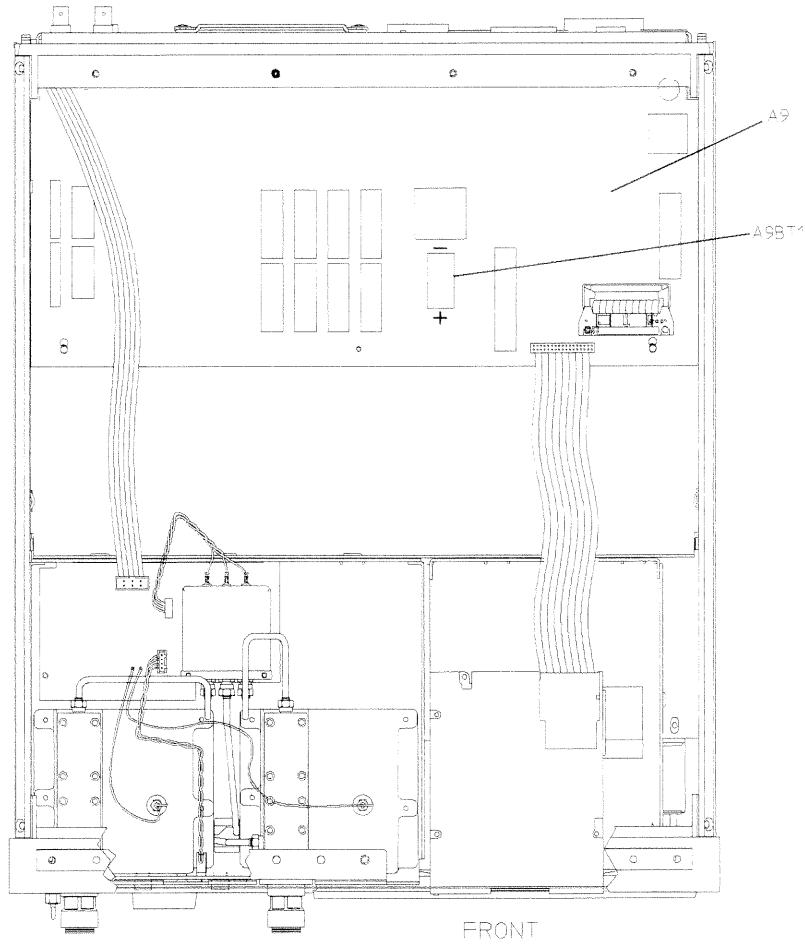
1. Remove the A9 CPU board (refer to “A9 CPU Board” in this chapter).
2. Unsolder and remove A9BT1 from the A9 CPU board.

Warning **Battery A9BT1 contains lithium. Do not incinerate or puncture this battery. Dispose of the discharged battery in a safe manner.**

Replacement

1. Make sure the new battery is inserted into the A9 board with the correct polarity.
2. Solder the battery into place.
3. Replace the A9 CPU board (refer to “A9 CPU Board” in this chapter).

A9BT1 Battery



sg6260D

A15 Preregulator

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap

Removal

1. Remove the rear panel (refer to “Rear Panel Assembly” in this chapter).
2. Disconnect the wire bundle (A15W1) from A8J2 and A17J3.
3. Remove the preregulator (A15) from the frame.

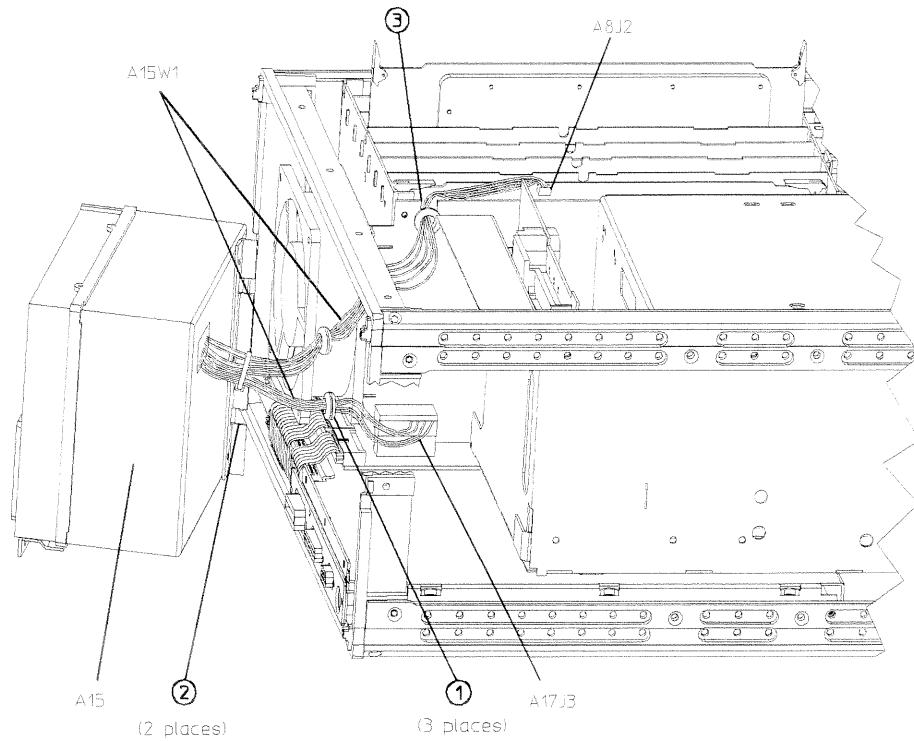
Replacement

1. Reverse the order of the removal procedure.

Note

- When reinstalling the preregulator (A15), make sure the three grommets (item 1) on A15W1 are seated in the two slots (item 2) on the back side of the preregulator and the slot (item 3) in the card cage wall.
 - After reinstalling the preregulator (A15), be sure to set the line voltage selector to the appropriate setting, 115 V or 230 V.
-

A15 Preregulator



sg660d

A16 Rear Panel Interface

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- 3/16-inch hex-nut driver
- 9/16-inch hex-nut driver
- ESD (electrostatic discharge) grounding wrist strap

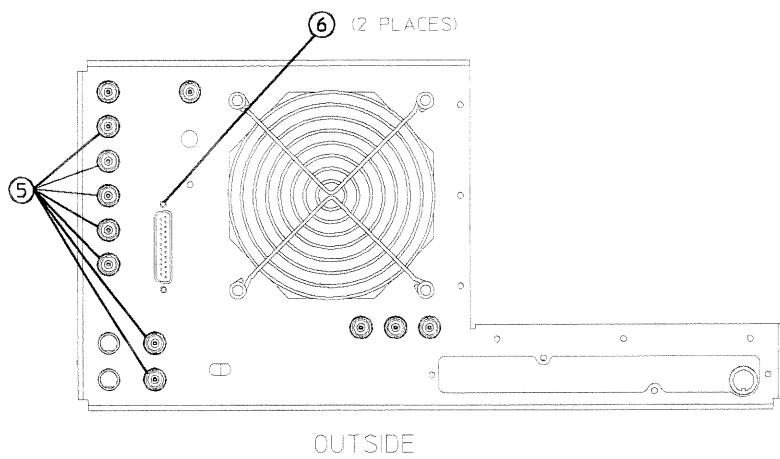
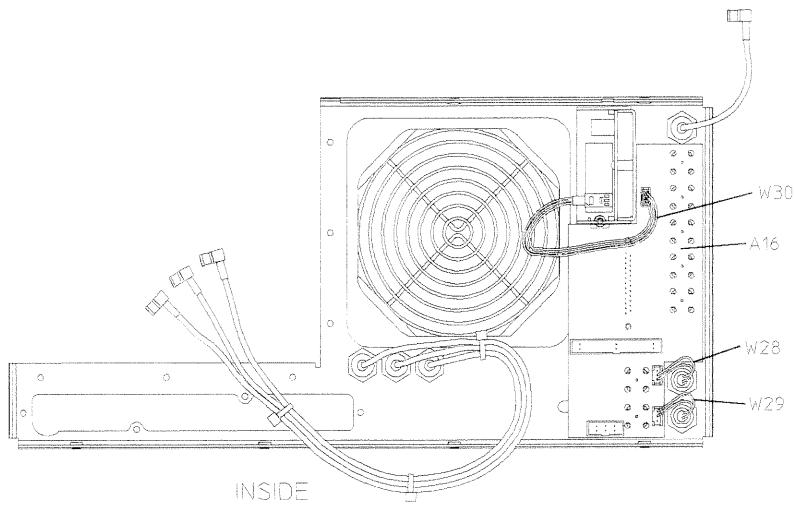
Removal

1. Remove the rear panel (refer to “Rear Panel Assembly” in this chapter).
2. Disconnect the fuse harnesses (W28 and W29) from the rear panel interface board (A16).
3. If you have Option 1D5, disconnect W30 from the rear panel interface board (A16).
4. Remove the hex nuts and washers from the BNC connectors (item 5) as shown.
5. Remove the two hex screws and washers that attach the test set-I/O interconnect (item 6). Remove the rear panel board (A16).

Replacement

1. Reverse the order of the removal procedure.

A16 Rear Panel Interface



sg664

A17 Motherboard Assembly

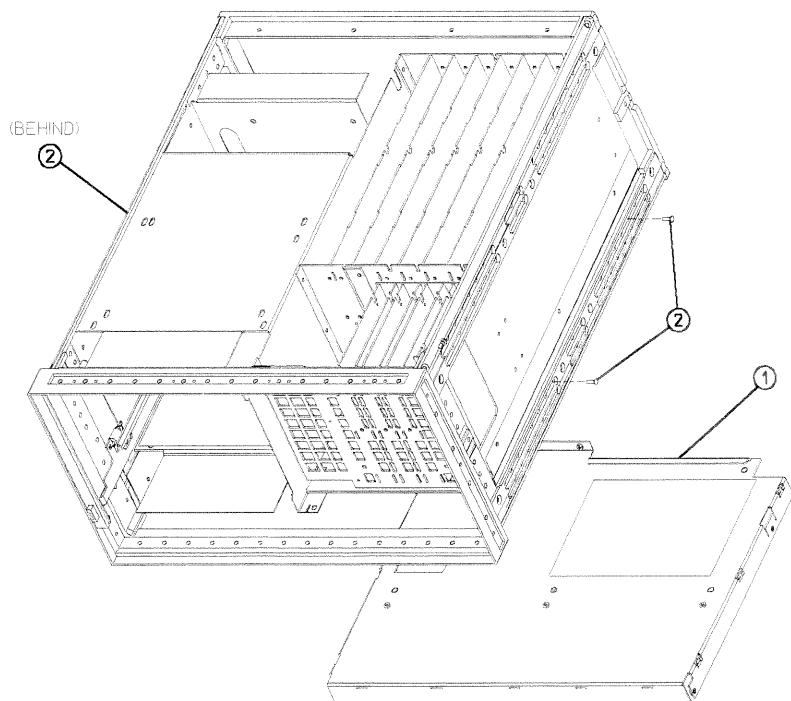
Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- T-20 TORX screwdriver
- small slot screwdriver
- 2.5-mm hex-key driver
- 5/16-inch open-end torque wrench (set to 10 in-lb)
- ESD (electrostatic discharge) grounding wrist strap

Removal

1. Disconnect the power cord and remove the top, bottom, and side covers (refer to “Covers” in this chapter).
2. Remove the front panel assembly (refer to “Front Panel Assembly” in this chapter).
3. Remove the rear panel assembly (refer to “Rear Panel Assembly” in this chapter).
4. Remove the preregulator (refer to “A15 Preregulator” in this chapter).
5. Remove the fan (refer to “B1 Fan” in this chapter).
6. Remove the graphics processor (refer to “A19 Graphics Processor” in this chapter).
7. Remove the test set deck (refer to “Test Set Deck” in this chapter).
8. Remove the disk drive deck (refer to “A20 Disk Drive” in this chapter).
9. Remove the CPU board (refer to “A9 CPU Board” in this chapter).
10. Remove the memory deck (item 1) by removing three screws (item 2) from the bottom corner struts of the motherboard/card cage assembly. There are two screws on the right side and one on the left side.

A17 Motherboard Assembly



sg694d

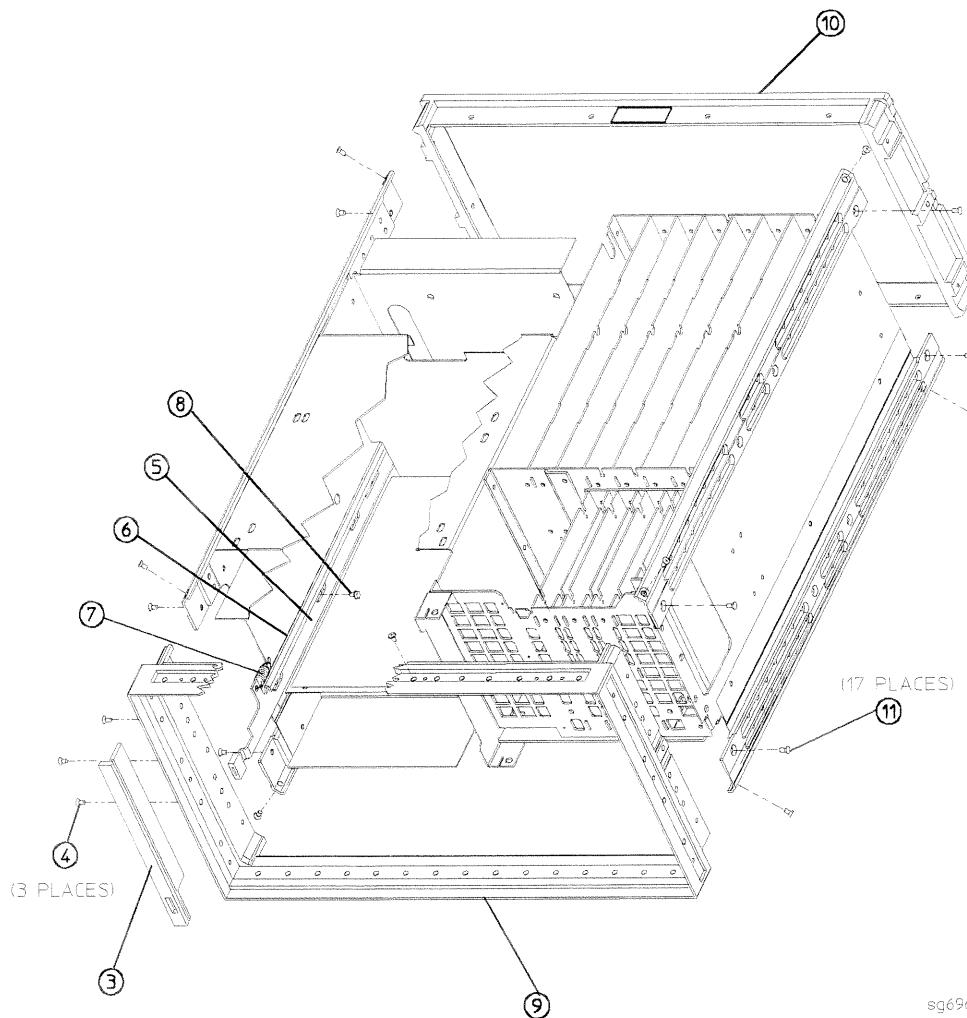
A17 Motherboard Assembly

11. Remove the display (refer to “A18 Display” in this chapter).
12. Remove the source assembly (refer to “A3 Source Assembly” in this chapter).
13. Remove the samplers and pulse generator (refer to “A4, A5, A6 Samplers and A7 Pulse Generator” in this chapter).
14. Remove the card cage boards (refer to “A8, A10, A11, A12, A13, A14 Card Cage Boards” in this chapter).
15. Remove the bezel support (item 3) by removing the three screws (item 4) from the left side of the front frame.
16. Remove the actuator assembly (item 5) and insulator strip (item 6) by unhooking the spring (item 7) and removing the screw (item 8) that secures them to the display housing.
17. Remove the front frame (item 9) and rear frame (item 10) by removing the attaching screws (item 11). At this point, only the motherboard/card cage assembly should remain. This whole assembly is replaceable.

Replacement

1. Reverse the order of the removal procedure.

A17 Motherboard Assembly



sg696d

A18 Display

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap

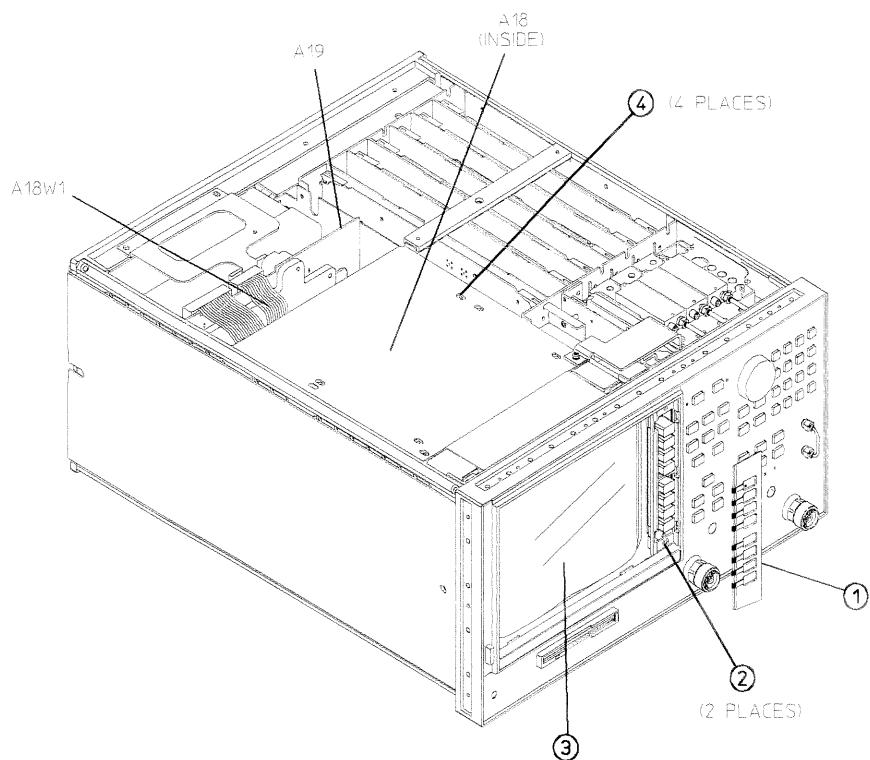
Removal

1. Disconnect the power cord.
2. Remove the bezel's softkey cover (item 1) by sliding your fingernail under the left edge, near the top or bottom of the cover. Pry the softkey cover away from the bezel. If you use another tool, take care not to scratch the glass.
3. Remove the two screws (item 2) exposed by the previous step. The bezel (item 3) is now free from the frame. Remove it.
4. Remove the top cover (refer to "Covers" in this chapter).
5. Disconnect the ribbon cable (A18W1) from the graphics processor board (A19).
6. Remove the four screws (item 4) on the top of the display housing.
7. Slide the display (A18) out of the instrument, pushing on the back of the display assembly. There is an opening at the rear of the display housing where you can reach in with a couple of fingers to push the display.

Replacement

1. Remove the bottom shield that is attached to the replacement display. Install the bottom shield on the old display assembly before you return it for repair.
2. Ensure the ribbon cable (A18W1) is connected to the display so you can retrieve it through the opening in the rear of the display housing when you reinstall the display.
3. Reverse the order of the removal procedure with the exception that the four screws (item 4) should not be tightened until after you have reinstalled the bezel assembly and pushed the display forward in the display housing so that it is firmly pressing against the bezel assembly.

A18 Display



sg662d

A19 Graphics Processor

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap

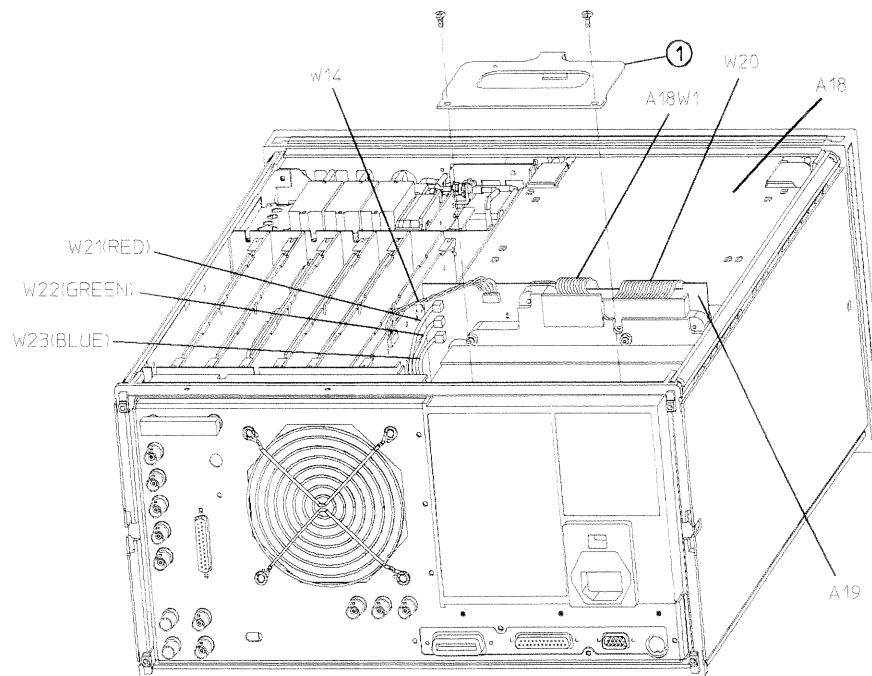
Removal

1. Disconnect the power cord and remove the top cover (refer to "Covers" in this chapter).
2. Remove the clip (item 1) that secures the graphics processor board (A19), removing the two screws that attach it to the rear frame. Gently press the top of the graphics processor board (A19) towards the display (A18), then lift up.
3. Disconnect the two ribbon cables (A18W1 and W20) and the wire bundle (W14) from the graphics processor board (A19).
4. Disconnect the three flexible cables (W21, W22, and W23) from the graphics processor board (A19). Remove the board.

Replacement

1. Reverse the order of the removal procedure.

A19 Graphics Processor



sg663d

A20 Disk Drive

Tools Required

- T-8 TORX screwdriver
- T-10 TORX screwdriver
- T-15 TORX screwdriver
- small slot screwdriver
- ESD (electrostatic discharge) grounding wrist strap

Removal

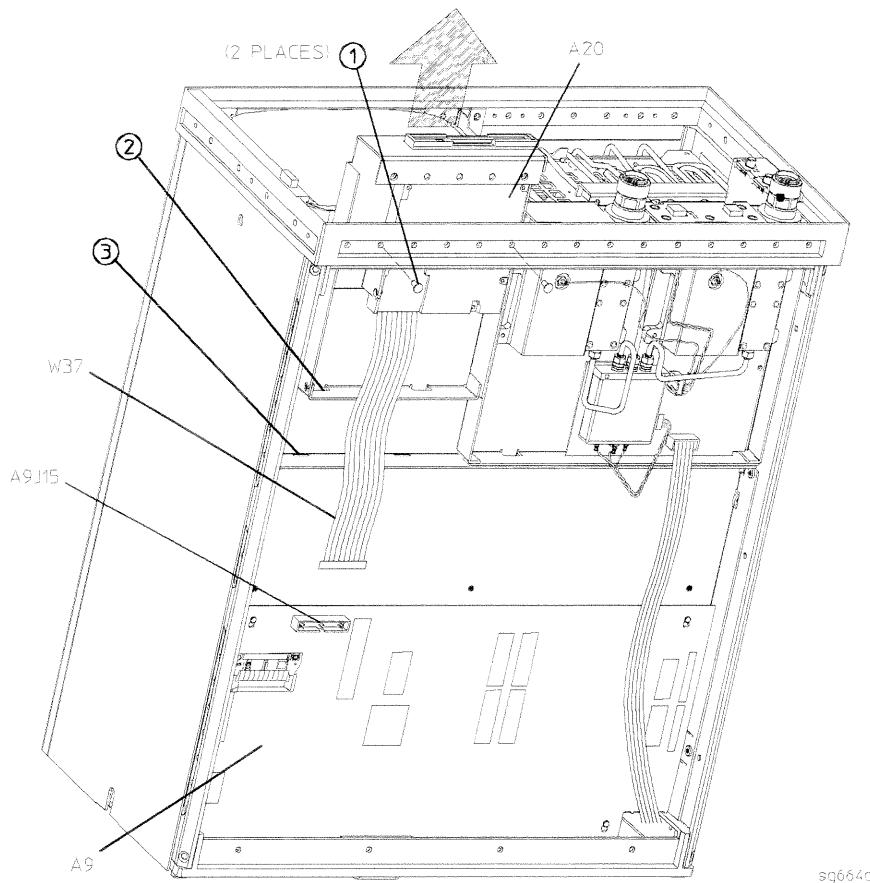
1. Disconnect the power cord and remove the bottom cover (refer to “Covers” in this chapter).
2. Remove the front panel (refer to “Front Panel Assembly” in this chapter).
3. Turn the instrument upside-down and disconnect the ribbon cable, W37, from the CPU board (A9J15).
4. Remove the two screws (item 1) that secure the disk drive deck to the bottom edge of the front frame.
5. Slide the disk drive deck out of the instrument.
6. Remove the four screws that secure the disk drive (A20) to the deck.
Remove the drive from the deck.

Replacement

1. Reverse the order of the removal procedure.

Note When replacing the disk drive deck, ensure that the two tabs (item 2) at the rear of the deck slide into the slots (item 3) of the CPU board deck.

A20 Disk Drive



D79956

A21, A22 Test Port Couplers

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- small slot screwdriver
- ESD (electrostatic discharge) grounding wrist strap
- 5/16-inch open-end torque wrench (set to 10 in-lb)

Removal

1. Remove the test set deck (refer to “Test Set Deck” in this chapter).
2. Disconnect the small bias wire from the test set interface board (A25).
For coupler A21 disconnect the blue wire (A21W1).
For coupler A22 disconnect the gray wire (A22W1).
3. Disconnect the two semi-rigid cables from the coupler assembly.
For coupler A21 disconnect W3 and W31.
For coupler A22 disconnect W4 and W32.
4. Remove the four screws, washers, and plastic shoulders that secure the coupler to the test set deck. Remove the coupler.

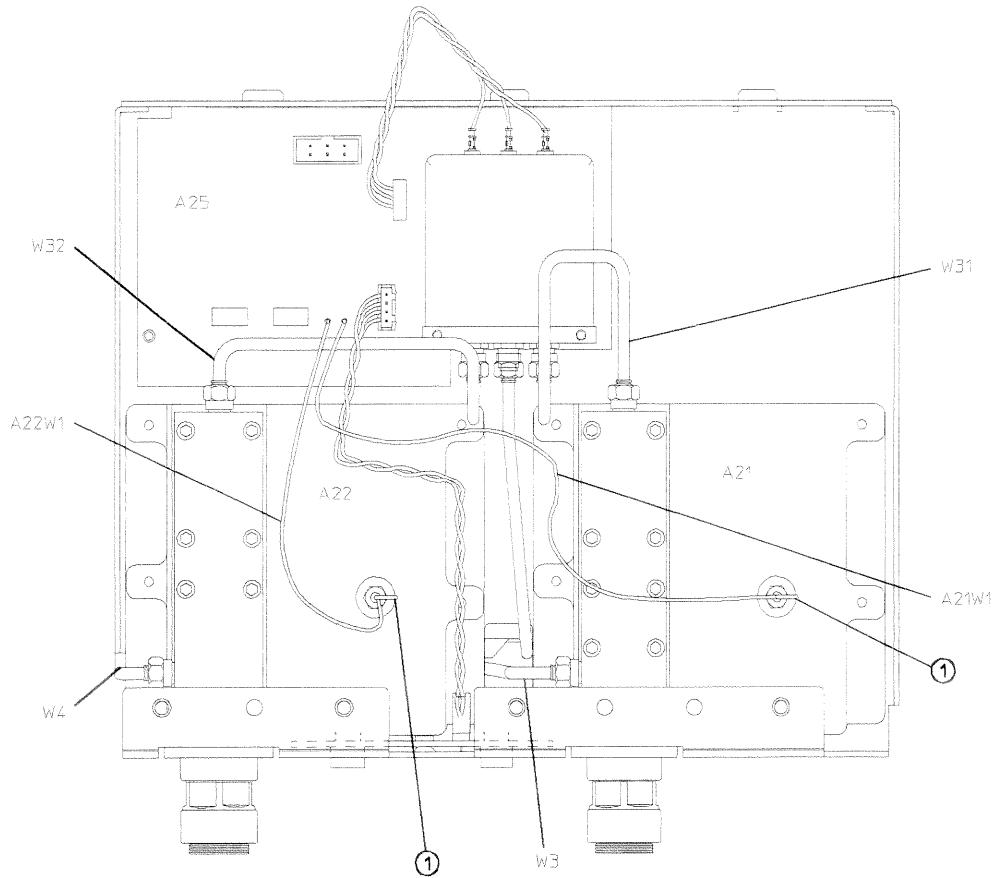
Replacement

1. Reverse the order of the removal procedure.

Note

- If you’re installing a new coupler, the gold lead on the feedthru capacitor (item 1) must be *carefully* bent at 90 degrees to prevent it from shorting to the bottom cover. You must also remove the small bias wire (A21W1 or A22W1) from the old coupler and solder it to the feedthru on the new coupler.
- When reconnecting semi-rigid cables, it is recommended that the connections be torqued to 10 in-lb.

A21, A22 Test Port Couplers



sg667d

A23 LED Board

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- small slot screwdriver
- ESD (electrostatic discharge) grounding wrist strap
- 5/16-inch open-end torque wrench (set to 10 in-lb)

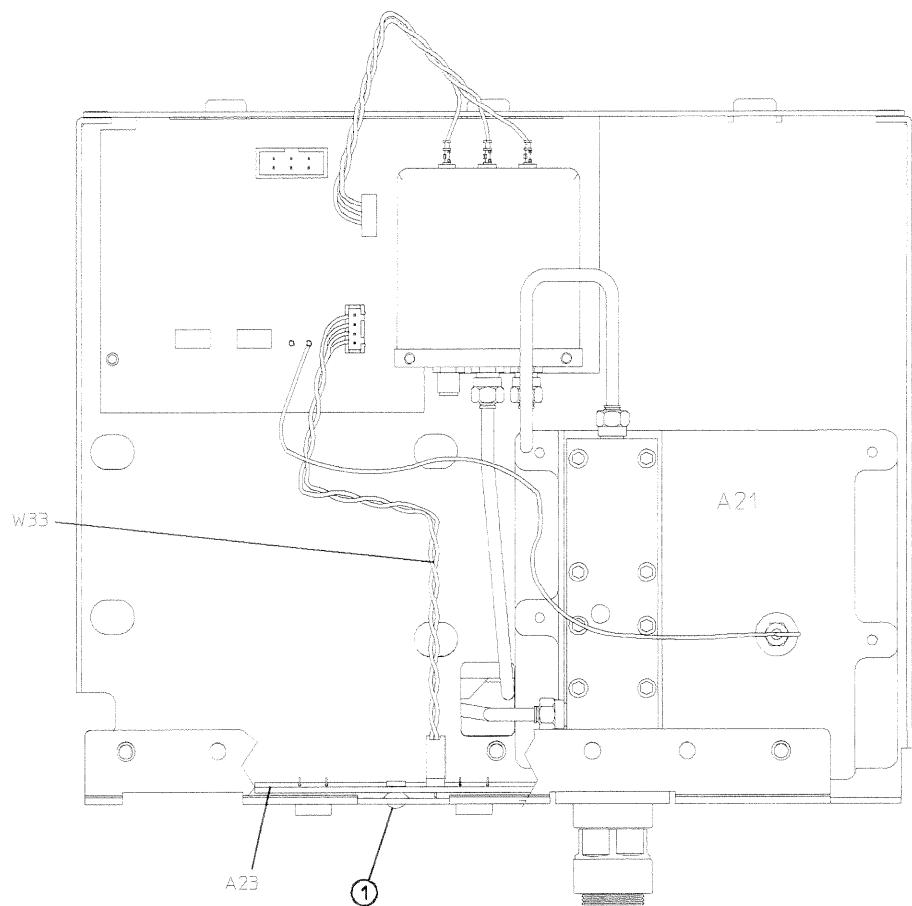
Removal

1. Remove the test set deck (refer to “Test Set Deck” in this chapter).
2. Remove the A22 test port coupler (refer to “A21, A22 Test Port Couplers” in this chapter).
3. Disconnect W33 from the LED board (A23).
4. Remove the screw (item 1) from the front of the test set deck.
5. Remove the LED board (A23), tilting the board back to clear the LEDs from the two square openings in front of the test set deck, and then lifting the board so that its tabs come out of two slots in the floor of the deck.

Replacement

1. Reverse the order of the removal procedure.

A23 LED Board



sg668d

A24 Transfer Switch

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- 5/16-inch open-end torque wrench (set to 10 in-lb)
- ESD (electrostatic discharge) grounding wrist strap

Removal

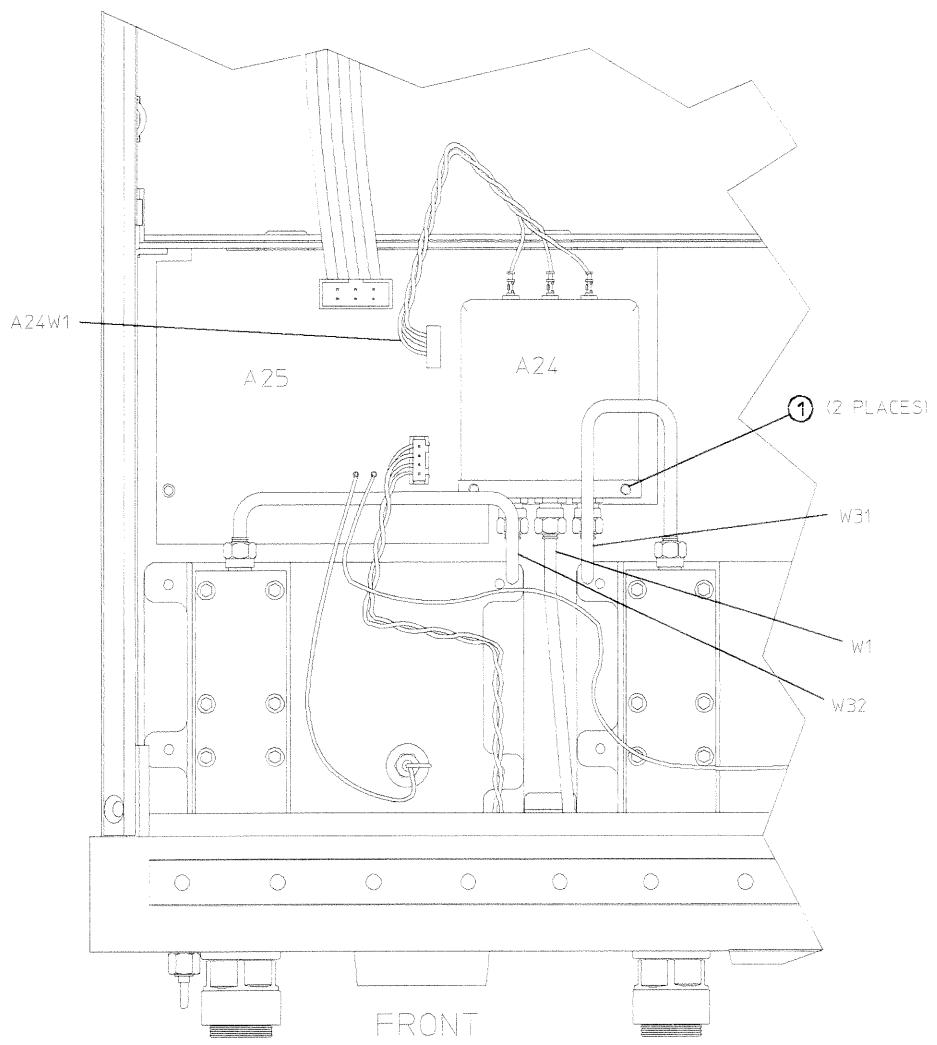
1. Disconnect the power cord and remove the bottom cover (refer to "Covers" in this chapter).
2. Disconnect A24W1 from the test set interface board (A25).
3. Disconnect the three semi-rigid cables (W1, W31, and W32) from the transfer switch (A24).
4. Remove the two screws (item 1) that secure the transfer switch.

Replacement

1. Reverse the order of the removal procedure.

Note	When reconnecting semi-rigid cables, it is recommended that the connections be torqued to 10 in-lb.
-------------	---

A24 Transfer Switch



sg669d

A25 Test Set Interface

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- 5/16-inch open-end torque wrench (set to 10 in-lb)
- ESD (electrostatic discharge) grounding wrist strap

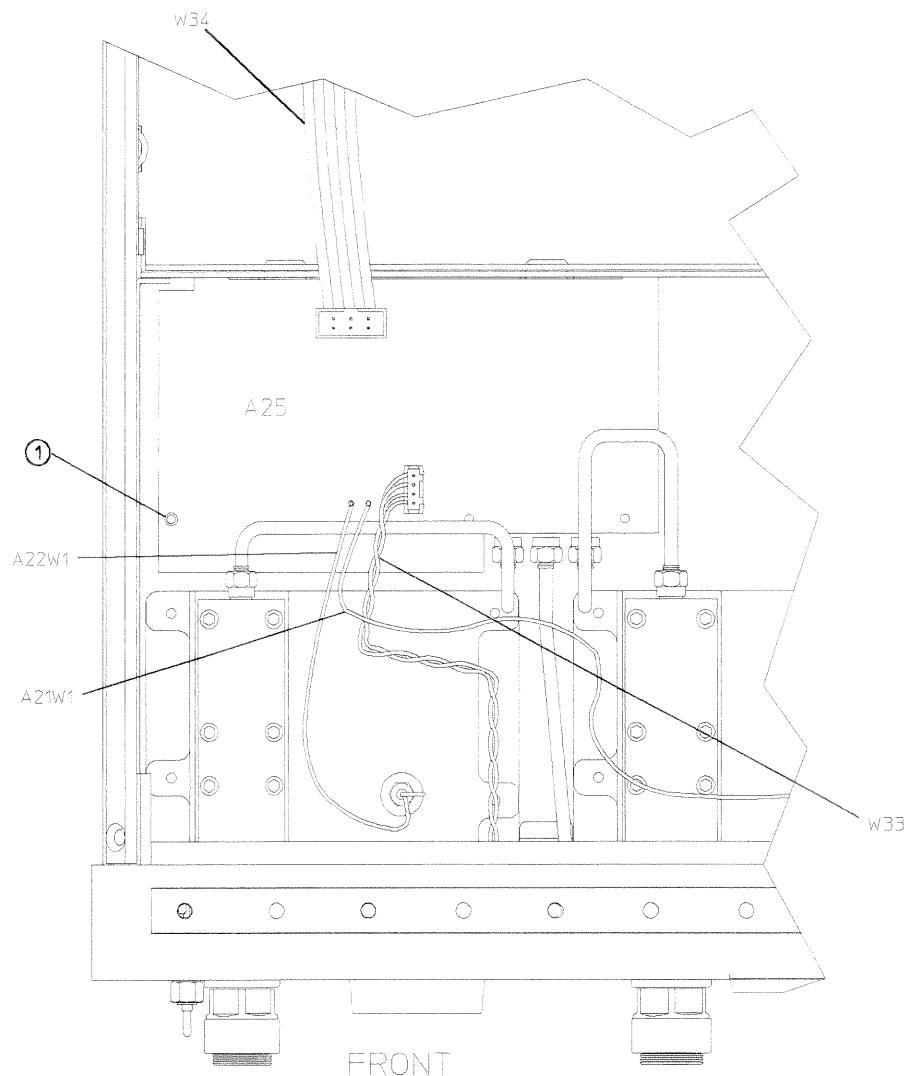
Removal

1. Remove the transfer switch (refer to “A24 Transfer Switch” in this chapter).
2. Disconnect all cables and wires (A21W1, A22W1, W33, and W34) from the test set interface board (A25).
3. Remove the screw (item 1) that secures the test set interface board.

Replacement

1. Reverse the order of the removal procedure.

A25 Test Set Interface



sg670d

A26 High Stability Frequency Reference (Option 1D5)

Tools Required

- T-10 TORX screwdriver
- T-15 TORX screwdriver
- 9/16-inch hex-nut driver
- ESD (electrostatic discharge) grounding wrist strap

Removal

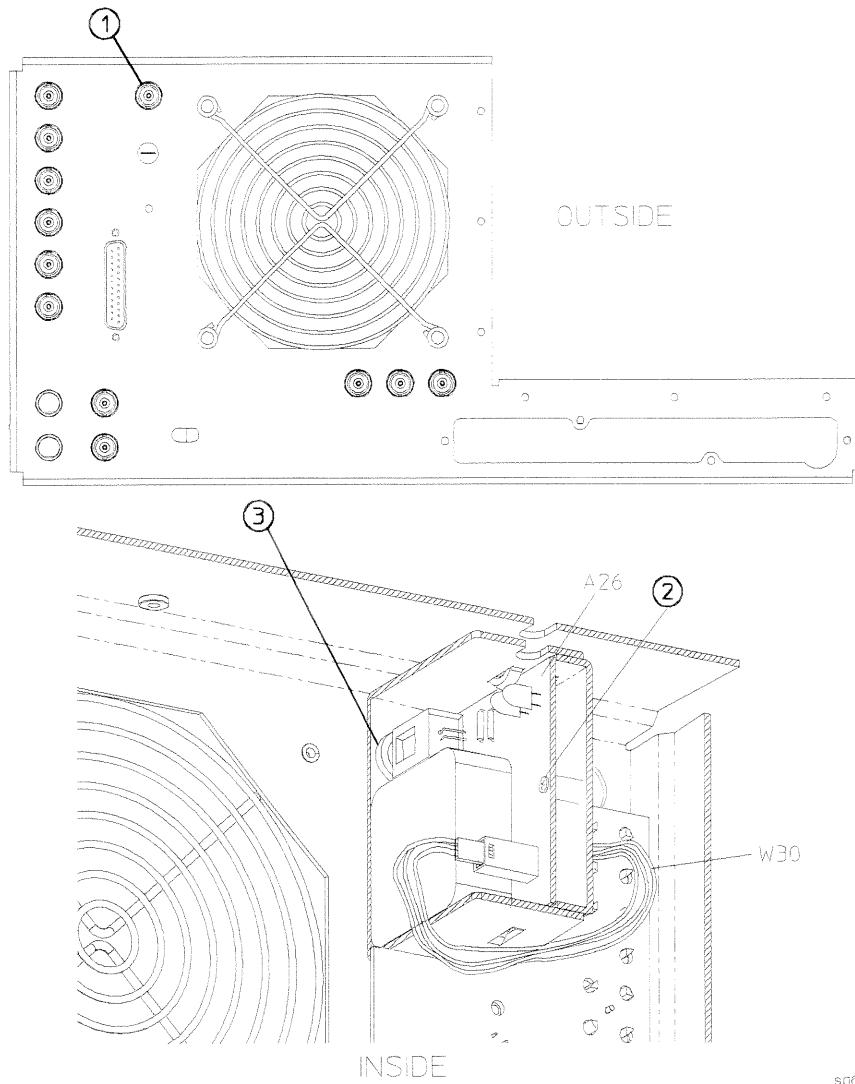
1. Remove the rear panel (refer to “Rear Panel Assembly” in this chapter).
2. Disconnect W30 from the high stability frequency reference board (A26).
3. Remove the BNC connector nut and washer from the “10 MHz PRECISION REFERENCE” connector (item 1) on the rear panel.
4. Remove the screw (item 2) that secures the high stability frequency reference board (A26) to the bracket.
5. Slide the board out of the bracket. Be careful not to lose the plastic spacer washer (item 3) that is on the BNC connector as the board is being removed.

Replacement

1. Reverse the order of the removal procedure.

Note	Before reinserting the high stability frequency reference board (A26) into the bracket, be sure the plastic spacer washer (item 3) is on the BNC connector.
-------------	---

A26 High Stability Frequency Reference (Option 1D5)



sg671d

B1 Fan

Tools Required

- 2.5-mm hex-key driver
- T-10 TORX screwdriver
- T-15 TORX screwdriver
- ESD (electrostatic discharge) grounding wrist strap

Removal

1. Remove the rear panel (refer to “Rear Panel Assembly” in this chapter).
2. Disconnect the fan harness (B1W1) from the motherboard (A17J5).
3. Remove the four screws and washers (item 1) that secure the fan (B1).

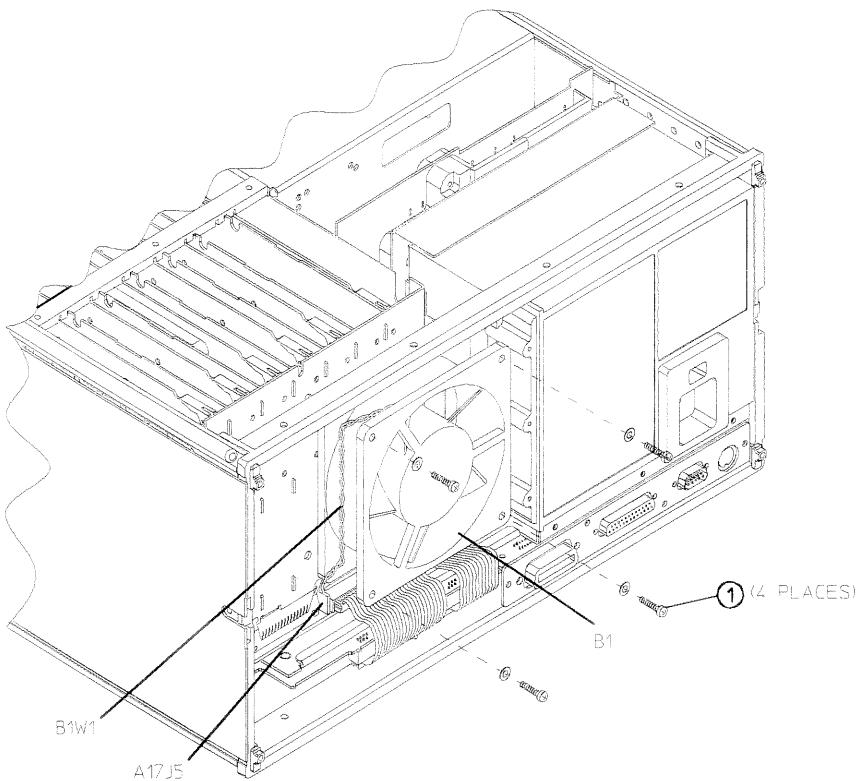
Replacement

1. Reverse the order of the removal procedure.

Note

The fan should be installed so that the direction of the air flow is away from the instrument. There is an arrow on the fan chassis indicating the air flow direction.

B1 Fan



sg672d

Post-Repair Procedures for HP 8753D

Table 14-1 lists the additional service procedures which you must perform to ensure that the instrument is working correctly, following the replacement of an assembly.

Perform the procedures in the order that they are listed in the table.

Table 14-1. Related Service Procedures

Replaced Assembly	Adjustments/ Correction Constants (CC)	Verification
A1 Front Panel Keyboard	None	Internal Test 0 Internal Test 23
A2 Front Panel Interface	None	Internal Test 0 Internal Test 23 Internal Test 12
A3 Source	A9 CC Jumper Positions Source Def CC (Test 44) Pretune Default CC (Test 45) Analog Bus CC (Test 46) Source Pretune CC (Test 48) RF Output Power CC (Test 47) Sampler Magnitude and Phase CC (Test 53) Cavity Oscillator Frequency CC (Test 54) Source Spur Avoidance Tracking EEPROM Backup Disk	Output Power Spectral Purity (harmonics and mixer spurs)
A4/A5/A6 Samplers	A9 CC Jumper Positions Sampler Magnitude and Phase CC (Test 53) IF Amplifier CC (Test 51) EEPROM Backup Disk	Minimum R Level (if R sampler replaced) Input Crosstalk Absolute Amplitude Accuracy Frequency Response
A7 Pulse Generator	A9 CC Jumper Positions Sampler Magnitude and Phase CC (Test 53) EEPROM Backup Disk	Frequency Response Frequency Range and Accuracy Spectral Purity (phase noise)
A8 Post Regulator	A9 CC Jumper Positions Cavity Oscillator Frequency CC (Test 54) Source Spur Avoidance Tracking EEPROM Backup Disk	Internal Test 0 Check A8 test point voltages

Table 14-1. Related Service Procedures (2 of 3)

Replaced Assembly	Adjustments/ Correction Constants (CC)	Verification
A9 CPU ¹	A9 CC Jumper Positions Serial Number CC (Test 55) Option Number CC (Test 56) Display Intensity and Focus CC (Test 49) Source Def CC (Test 44) Pretune Default CC (Test 45) Analog Bus CC (Test 46) Cal Kit Default (Test 57) Source Pretune CC (Test 48) RF Output Power CC (Test 47) Sampler Magnitude and Phase CC (Test 53) ADC Linearity CC (Test 52) IF Amplifier CC (Test 51) Cavity Oscillator Frequency CC (Test 54) EEPROM Backup Disk	Output Power Absolute Amplitude Accuracy Frequency Response Dynamic Accuracy
Firmware Rev 5.20 08753-60185	A9 CC Jumper Positions Source Default CC (Test 44) Pretune Default CC (Test 45) Analog Bus CC (Test 46) RF Output Power Correction Constants (Test 47) Source Pretune CC (Test 48) Sampler Magnitude and Phase CC (Test 53) EEPROM Backup Disk	Internal Test 0
A10 Digital IF	A9 CC Jumper Positions Analog Bus CC (Test 46) Sampler Magnitude and Phase CC (Test 53) ADC Linearity CC (Test 52) IF Amplifier CC (Test 51) EEPROM Backup Disk	Receiver Noise Level Trace Noise Input Crosstalk Absolute Amplitude Accuracy
A11 Phase Lock	A9 CC Jumper Positions Analog Bus CC (Test 46) Pretune Default CC (Test 45) Source Pretune CC (Test 48) EEPROM Backup Disk	Minimum R Level Frequency Accuracy

1 If you have an EEPROM backup disk available, you only need to perform the first three tests listed.

Table 14-1. Related Service Procedures (3 of 3)

Replaced Assembly	Adjustments/ Correction Constants (CC)	Verification
A12 Reference	A9 CC Jumper Positions High/Low Band Transition Frequency Accuracy EEPROM Backup Disk	Frequency Range and Accuracy
A13 Fractional-N (Analog)	A9 CC Jumper Positions Fractional-N Spur and FM Sideband EEPROM Backup Disk	Spectral Purity (other spurious signals) Frequency Range and Accuracy
A14 Fractional-N (Digital)	A9 CC Jumper Positions Fractional-N Frequency Range Fractional-N Spur Avoidance and FM Sideband EEPROM Backup Disk	Frequency Range and Accuracy
A15 Preregulator	None	Self-Test
A16 Rear Panel Interface	None	Internal Test 13, Rear Panel
A17 Motherboard	None	Self-Test
A18 Display	Vertical Position and Focus Display Intensity (Test 49) (only if needed)	Observation of Display Tests 66 - 80
A19 Graphics System Processor	None	Observation of Display Tests 59 - 80

14-62 Assembly Replacement and Post-Repair Procedures

Safety and Licensing

Notice

The information contained in this document is subject to change without notice.

Hewlett-Packard makes no warranty of any kind with regard to this material, including but not limited to, the implied warranties of merchantability and fitness for a particular purpose. Hewlett-Packard shall not be liable for errors contained herein or for incidental or consequential damages in connection with the furnishing, performance, or use of this material.

Certification

Hewlett-Packard Company certifies that this product met its published specifications at the time of shipment from the factory. Hewlett-Packard further certifies that its calibration measurements are traceable to the United States National Institute of Standards and Technology, to the extent allowed by the Institute's calibration facility, and to the calibration facilities of other International Standards Organization members.

Warranty

This Hewlett-Packard instrument product is warranted against defects in material and workmanship for a period of one year from date of shipment. During the warranty period, Hewlett-Packard Company will, at its option, either repair or replace products which prove to be defective.

For warranty service or repair, this product must be returned to a service facility designated by Hewlett-Packard. Buyer shall prepay shipping charges to Hewlett-Packard and Hewlett-Packard shall pay shipping charges to return the product to Buyer. However, Buyer shall pay all shipping charges, duties, and taxes for products returned to Hewlett-Packard from another country.

Hewlett-Packard warrants that its software and firmware designated by Hewlett-Packard for use with an instrument will execute its programming instructions when properly installed on that instrument. Hewlett-Packard does not warrant that the operation of the instrument, or software, or firmware will be uninterrupted or error-free.

LIMITATION OF WARRANTY

The foregoing warranty shall not apply to defects resulting from improper or inadequate maintenance by Buyer, Buyer-supplied software or interfacing, unauthorized modification or misuse, operation outside of the environmental specifications for the product, or improper site preparation or maintenance.

NO OTHER WARRANTY IS EXPRESSED OR IMPLIED. HEWLETT-PACKARD SPECIFICALLY DISCLAIMS THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE.

EXCLUSIVE REMEDIES

THE REMEDIES PROVIDED HEREIN ARE BUYER'S SOLE AND EXCLUSIVE REMEDIES. HEWLETT-PACKARD SHALL NOT BE LIABLE FOR ANY DIRECT, INDIRECT, SPECIAL, INCIDENTAL, OR CONSEQUENTIAL DAMAGES, WHETHER BASED ON CONTRACT, TORT, OR ANY OTHER LEGAL THEORY.

Assistance

Product maintenance agreements and other customer assistance agreements are available for Hewlett-Packard products.

For any assistance, contact your nearest Hewlett-Packard Sales and Service Office.

Table 15-1. Hewlett-Packard Sales and Service Offices

US FIELD OPERATIONS		
Headquarters Hewlett-Packard Co. 19320 Pruneridge Avenue Cupertino, CA 95014 (800) 752-0900	California, Northern Hewlett-Packard Co. 301 E. Evelyn Mountain View, CA 94041 (415) 694-2000	California, Southern Hewlett-Packard Co. 1421 South Manhattan Ave. Fullerton, CA 92631 (714) 999-6700
Colorado Hewlett-Packard Co. 24 Inverness Place, East Englewood, CO 80112 (303) 649-5512	Atlanta Annex Hewlett-Packard Co. 2124 Barrett Park Drive Kennesaw, GA 30144 (404) 648-0000	Illinois Hewlett-Packard Co. 5201 Tollview Drive Rolling Meadows, IL 60008 (708) 255-9800
New Jersey Hewlett-Packard Co. 150 Green Pond Rd. Rockaway, NJ 07866 (201) 586-5400	Texas Hewlett-Packard Co. 930 E. Campbell Rd. Richardson, TX 75081 (214) 231-6101	
EUROPEAN FIELD OPERATIONS		
Headquarters Hewlett-Packard S.A. 150, Route du Nant-d'Avril 1217 Meyrin 2/Geneva Switzerland (41 22) 780.8111	France Hewlett-Packard France 1 Avenue Du Canada Zone D'Activite De Courtaboeuf F-91947 Les Ulis Cedex France (33 1) 69 82 60 60	Germany Hewlett-Packard GmbH Hewlett-Packard Strasse 61352 Bad Homburg v.d.H Germany (49 6172) 16-0
Great Britain Hewlett-Packard Ltd. Eskdale Road, Winnersh Triangle Wokingham, Berkshire RG41 5DZ England (44 734) 696622		

Table 15-1.
Hewlett-Packard Sales and Service Offices (continued)

INTERCON FIELD OPERATIONS		
Headquarters	Australia	Canada
Hewlett-Packard Company 3495 Deer Creek Road Palo Alto, California, USA 94304-1316 (415) 857-5027	Hewlett-Packard Australia Ltd. 31-41 Joseph Street Blackburn, Victoria 3130 (61 3) 895-2895	Hewlett-Packard (Canada) Ltd. 17500 South Service Road Trans-Canada Highway Kirkland, Quebec H9J 2X8 Canada (514) 697-4232
China	Japan	Singapore
China Hewlett-Packard Company 38 Bei San Huan X1 Road Shuang Yu Shu Hai Dian District Beijing, China (86 1) 256-6888	Hewlett-Packard Japan, Ltd. 1-27-15 Yabe, Sagamihara Kanagawa 229, Japan (81 427) 59-1311	Hewlett-Packard Singapore (Pte.) Ltd. 150 Beach Road #29-00 Gateway West Singapore 0718 (65) 291-9088
Taiwan		
Hewlett-Packard Taiwan 8th Floor, H-P Building 337 Fu Hsing North Road Taipei, Taiwan (886 2) 712-0404		

Shipment for Service

If you are sending the instrument to Hewlett-Packard for service, ship the analyzer to the nearest HP service center for repair, including a description of any failed test and any error message. Ship the analyzer, using the original or comparable anti-static packaging materials. A listing of Hewlett-Packard sales and service offices in Table 15-1.

15-4 Safety and Licensing

Safety Symbols

The following safety symbols are used throughout this manual. Familiarize yourself with each of the symbols and its meaning before operating this instrument.

Caution	Caution denotes a hazard. It calls attention to a procedure that, if not correctly performed or adhered to, would result in damage to or destruction of the instrument. Do not proceed beyond a caution note until the indicated conditions are fully understood and met.
Warning	Warning denotes a hazard. It calls attention to a procedure which, if not correctly performed or adhered to, could result in injury or loss of life. Do not proceed beyond a warning note until the indicated conditions are fully understood and met.

Instrument Markings



The instruction documentation symbol. The product is marked with this symbol when it is necessary for the user to refer to the instructions in the documentation.

“CE” The CE mark is a registered trademark of the European Community. (If accompanied by a year, it is when the design was proven.)

“ISM1-A” This is a symbol of an Industrial Scientific and Medical Group 1 Class A product.

“CSA” The CSA mark is a registered trademark of the Canadian Standards Association.

General Safety Considerations

Safety Earth Ground

Warning	This is a Safety Class I product (provided with a protective earthing ground incorporated in the power cord). The mains plug shall only be inserted in a socket outlet provided with a protective earth contact. Any interruption of the protective conductor, inside or outside the instrument, is likely to make the instrument dangerous. Intentional interruption is prohibited.
----------------	---

Before Applying Power

Caution	Make sure that the analyzer line voltage selector switch is set to the voltage of the power supply and the correct fuse is installed.
----------------	---

Caution	If this product is to be energized via an autotransformer make sure the common terminal is connected to the neutral (grounded side of the mains supply).
----------------	--

Servicing

Warning	No operator serviceable parts inside. Refer servicing to qualified personnel. To prevent electrical shock, do not remove covers.
----------------	--

Warning	These servicing instructions are for use by qualified personnel only. To avoid electrical shock, do not perform any servicing unless you are qualified to do so.
----------------	--

Warning	The opening of covers or removal of parts is likely to expose dangerous voltages. Disconnect the instrument from all voltage sources while it is being opened.
----------------	--

-
- Warning** Adjustments described in this document may be performed with power supplied to the product while protective covers are removed. Energy available at many points may, if contacted, result in personal injury.
-
- Warning** The power cord is connected to internal capacitors that may remain live for 10 seconds after disconnecting the plug from its power supply.
-
- Warning** For continued protection against fire hazard replace line fuse only with same type and rating (3 A 250 V F). The use of other fuses or material is prohibited.
-

Index

1

- 100 kHz pulses, 7-15
- 10 MHz HI OUT Waveform from A14J1, 7-25
- 10 MHz precision reference assembly replacement, 14-56 part numbers, 13-26
- 1st LO signal at sampler/mixer, 8-14

2

- 25 MHz HI OUT Waveform from A14J1, 7-26
- 2nd IF (4 kHz) signal locations, 8-11
- 2nd LO locations, 8-14
- 2ND LO waveforms, 7-20

4

- 4 kHz signal check, 8-11
- 4 MHz reference signal, 7-19
- 4 MHz REF signal check, 8-7

5

- +5 V digital supply theory of operation, 12-6

6

- 60 MHz HI OUT Waveform from A14J1, 7-26

8

- 8753D theory of operation, 12-1

A

- A10 assembly signals required, 8-8
- A10 check by substitution or signal examination, 8-8
- A10 digital IF, 12-29 digital control, 12-10
- A10 Digital IF, 10-33
- A11 input signals, 7-35
- A11 Input Signals, 7-35
- A11 phase lock, 10-34 source, 12-14
- A11 phase lock and A3 source check, 7-7
- A11 phase lock check, 7-34
- A12 digital control signals check, 7-22
- A12 reference, 10-40 source, 12-13
- A12 reference check, 7-12
- A13/A14 Fractional-N Check, 7-23
- A13 frac-N analog source, 12-13
- A14 Divide-by-N Circuit Check, 7-28
- A14 frac-N digital source, 12-13
- A14 fractional-N (digital), 10-43
- A14 generated digital control signals, 7-30
- A14-to-A13 digital control signals check, 7-28
- A14 VCO exercise, 7-26
- A15 preregulator

- theory of operation, 12-5
- A15 preregulator check, 5-9
- A15W1 plug detail, 5-10
- A16 rear panel
 - digital control, 12-12
- A18 display
 - digital control, 12-11
 - power, 12-8
- A18 display operation check, 6-7
- A19 GSP
 - digital control, 12-11
- A19 GSP and A18 display operation check, 6-7
- A19 power supply voltages for display, 6-13
- A19 walking one pattern, 6-15
- A1/A2 front panel troubleshooting, 6-7
- A1 front panel
 - digital control, 12-10
- A21 test port coupler, 12-25
- A22 test port coupler, 12-25
- A23 LED front panel, 12-25
- A24 transfer switch, 12-25
- A25 test set interface, 12-25
- A2 front panel processor
 - digital control, 12-10
- A3 source
 - external source mode, 12-22
 - frequency offset, 12-21
 - harmonic analysis, 12-21
 - high band theory, 12-18
 - low band theory, 12-15
 - operation in other modes, 12-21
 - source, 12-14
 - super low band theory, 12-14
 - theory of operation, 12-2, 12-13
 - tuned receiver mode, 12-24
- A3 source and A11 phase lock check, 7-7
- A4 sampler/mixer, 12-28
- A4 sampler/mixer check, 7-6
- A5 sampler/mixer, 12-28
- A6 sampler/mixer, 12-28
- A7 pulse generator
 - source, 12-14
- A7 pulse generator check, 7-31
- A8 fuses and voltages, 5-14
- A8 post regulator
 - air flow detector, 12-7
 - display power, 12-8
 - green LEDs, 12-7
 - probe power, 12-8
 - shutdown circuit, 12-7
 - theory of operation, 12-7
 - variable fan circuit, 12-7
- A8 post regulator test points, 5-5
- A9 CC jumper positions, 10-8
- A9 CPU
 - digital control, 12-10
- A9 CPU operation check, 6-4
- A and B inputs check, 8-4
- A and B input traces check, 4-15
- ABUS Cor., 10-13
- ABUS node 16 for power check, 4-14
- ABUS Test., 10-10
- accessories error messages check, 4-18
- accessories inspection, 9-3
- accessories troubleshooting, 4-18
- accessories troubleshooting chapter, 9-1
- accuracy and range of frequency, 2-23
- accuracy of frequency adjustment, 3-50
- accuracy of power test, 2-28
- adapters, 1-3
- ADC Hist., 10-11
- ADC Lin., 10-10
- ADC main, 10-23

Index-2

ADC offset correction constants
adjustment, 3-20
ADC Of., 10-10
ADC Of Cor., 10-13
ADD, 10-6
addresses for HP-IB systems, 4-5
adjustment
 A9 CC Jumper Positions, 3-6
 ADC offset correction constants
 (test 52), 3-20
 analog bus correction constants
 (test 46), 3-9
 calibration kit default correction
 constants (test 57), 3-40
 cavity oscillator frequency
 correction constants (test 54),
 3-31
 display degaussing (demagnetizing),
 3-46
 display intensity correction
 constants (test 49), 3-15
fractional-N frequency range, 3-47
fractional-N spur avoidance and
 FM sideband, 3-56
frequency accuracy, 3-50
high/low band transition, 3-54
IF amplifier correction constants
 (test 51), 3-19
initialize EEPROMs (test 58), 3-41
option numbers correction constants
 (test 56), 3-39
RF output power correction
 constants (test 47), 3-10
sampler magnitude correction
 constants (test 53), 3-21
sequences for mechanical
 adjustments, 3-64
serial number correction constants
 (test 55), 3-37
source default correction constants
 (test 44), 3-7
source pretune correction constants
 (test 48), 3-14
source pretune default correction
 constants (test 45), 3-8
source spur avoidance tracking,
 3-60
 vertical position and focus, 3-44
adjustments analyzer, 3-1
adjustment tests, 10-3
Adjustment Tests, 10-13
ADJUSTMENT TESTS, 10-5
air flow detector, 12-7
ALC ON OFF, 10-19
ALL INT, 10-7
ALT and NRM jumper position
 adjustment, 3-6
ALTER and NORMAL jumper position
 adjustment, 3-6
amplifier (IF) adjustment, 3-19
analog bus, 10-22
ANALOG BUS, 10-25
analog bus check of reference
 frequencies, 7-12
analog bus checks YO coil drive, 7-10
analog bus codes, 10-49
analog bus correction constants
 adjustment, 3-9
analog bus node 1, 10-27
analog bus node 11, 10-34
analog bus node 12, 10-34
analog bus node 13,14, 10-35
analog bus node 15, 10-36
analog bus node 16, 10-37
analog bus node 17, 10-38
analog bus node 18, 10-39
analog bus node 19, 10-39
analog bus node 2, 10-28
analog bus node 20, 10-40
analog bus node 21, 10-41
analog bus node 23, 10-41
analog bus node 24, 10-42

analog bus node 27, 10-43
analog bus node 29, 10-44
analog bus node 3, 10-29
analog bus node 30, 10-45
analog bus node 4, 10-30
analog bus node 5, 10-31
analog bus node 6, 10-31
analog bus node 7, 10-32
analog bus node 8, 10-32
analog bus node 9, 10-33
analog bus nodes, 10-26
 A3, 10-26
ANALOG BUS ON OFF, 10-22
analog in menu, 10-24
analog node 10, 10-33
analyzer
 theory of operations, 12-1
analyzer adjustments, 3-1
analyzer block diagram, 4-19
analyzer HP-IB address, 4-5
analyzer options available, 1-6
analyzer (spectrum), 1-2
analyzer verification, 2-1
antistatic wrist strap, 1-3
antistatic wrist strap and cord, 1-3
antistatic wrist strap cord, 1-3
appendix for source group
 troubleshooting, 7-37
assemblies
 bottom view, 13-8
 part numbers, 13-6-8
 rebuilt-exchange, 13-3
 replacement procedures. *See*
 assembly replacement
 top view, 13-6
assembly replacement, 14-1
 A10 digital IF, 14-28
 A11 phase lock, 14-28
 A12 reference, 14-28
 A13 frac-N analog, 14-28
 A14 frac-N digital, 14-28
 A15 preregulator, 14-34
 A16 rear panel interface, 14-36
 A17 motherboard, 14-38
 A18 display, 14-42
 A19 graphics processor, 14-44
 A1 keyboard, 14-20
 A20 disk drive, 14-46
 A21 test port-1 coupler, 14-48
 A22 test port-2 coupler, 14-48
 A23 LED board, 14-50
 A24 transfer switch, 14-52
 A25 test set interface, 14-54
 A26 high stability frequency
 reference, 14-56
 A2 front panel interface, 14-22
 A3 source, 14-24
 A4 R-sampler, 14-26
 A5 A-sampler, 14-26
 A6 B-sampler, 14-26
 A7 pulse generator, 14-26
 A8 post regulator, 14-28
 A9BT1 battery, 14-32
 A9 CPU, 14-30
 B1 fan, 14-58
 covers, 14-6
 front panel, 14-8
 line fuse, 14-4
 rear panel, 14-12
 test set desk, 14-16
attenuator
 theory of operation, 12-2
attenuators (fixed), 1-2
attenuator (step), 1-2
AUX OUT ON OFF, 10-24
available options, 1-6

B

background intensity adjustment for
 display, 3-15
backup EEPROM disk, 3-42
bad cables, 9-1

B and A inputs check, 8-4
band (high/low) transition adjustment, 3-54
BATTERY FAILED. STATE MEMORY CLEARED, 10-50
BATTERY LOW! STORE SAVE REGS TO DISK, 10-50
block diagram, 4-19
 digital control group, 6-4
 power supply, 5-23
 power supply functional group, 5-3
broadband power problems, 7-38
built-in test set, 12-25
 LED front panel, 12-25
 test port couplers, 12-25
 test set interface, 12-25
 transfer switch, 12-25
bulk tape eraser or demagnetizer, 1-2
bus
 analog, 10-22
bus nodes, 10-26

C

cable inspection, 6-10
cables, 1-3
 bottom view, 13-12
 front view, 13-14
 part numbers, 13-10-18
 rear view, 13-16
 source, 13-18
 top view, 13-10
cable test, 9-5
Cal Coef 1-12., 10-12
CAL FACTOR SENSOR A, 10-6
CAL FACTOR SENSOR B, 10-6
CALIBRATION ABORTED, 10-50
calibration certificate, 2-2
calibration coefficients, 11-1
calibration device inspection, 9-3
calibration kit 7 mm, 50Ω, 1-2
calibration kit default correction constants adjustment, 3-40
calibration kit device verification, 9-4
calibration kit Type-N, 75Ω, 1-2
calibration procedure, 11-3
CALIBRATION REQUIRED, 10-51
Cal Kit Def., 10-14
care of connectors, 1-4
CAUTION
 OVERLOAD ON INPUT A, POWER REDUCED, 8-3
 OVERLOAD ON INPUT B, POWER REDUCED, 8-3
 OVERLOAD ON INPUT R, POWER REDUCED, 8-3
cavity oscillator frequency adjustment, 3-31
cavity oscillator frequency correction constants adjustment, 3-31
Cav osc Cor., 10-13
CC procedures
 ADC offset (test 52), 3-20
 analog bus (test 46), 3-9
 calibration kit default (test 57), 3-40
 cavity oscillator frequency (test 54), 3-31
 display intensity (test 49), 3-15
 IF amplifier (test 51), 3-19
 initialize EEPROMs (test 58), 3-41
 option numbers (test 56), 3-39
 retrieve correction constant data from EEPROM backup disk, 3-43
 RF output power (test 47), 3-10
 sampler magnitude (test 53), 3-21
 serial number (test 55), 3-37
 source default (test 44), 3-7

source pretune default (test 45),
 3-8
source pretune (test 48), 3-14
Unprotected Hardware Option
 Numbers, 3-62
center conductor damage, 9-3
certificate of calibration, 2-2
certification of kit, 2-5
chassis
 part numbers, 13-40-42
check
 1st LO signal at sampler/mixer,
 8-14
 4 MHz REF signal, 8-7
 A10 by substitution or signal
 examination, 8-8
 A11 phase lock, 7-34
 A12 digital control signals, 7-22
 A12 reference, 7-12
 A13/A14 Fractional-N, 7-23
 A14 Divide-by-N Circuit Check,
 7-28
 A14-to-A13 digital control signals,
 7-28
 A15 Preregulator, 5-9
 A19 GSP and A18 display operation,
 6-7
 A1/A2 front panel, 6-7
 A3 source and A11 phase lock, 7-7
 A4 sampler/mixer, 7-6
 A7 pulse generator, 7-31
 A8 fuses and voltages, 5-14
 A9 CPU control, 6-4
 A and B inputs, 8-4
 A and B input traces, 4-15
 accessories error messages, 4-18
 CPU control, 6-4
 digital control, 4-10
 disk drive, 4-6
 fan voltages, 5-21
 FN LO at A12, 7-18

for a faulty assembly, 5-11
GSP and A18 display operation,
 6-7
HP-IB systems, 4-5
line voltage, selector switch, fuse,
 5-7
motherboard, 5-13
operating temperature, 5-13
operation of A19 GSP and A18
 display, 6-7
operation of A9 CPU, 6-4
operator's, 4-4
phase lock error message, 7-4
phase lock error messages, 4-12
plotter or printer, 4-6
post regulator voltages, 5-5
power supply, 4-9
power supply voltages for display,
 6-13
power up sequence, 4-10
preregulator LEDs, 4-9
rear panel LEDs, 4-9
receiver, 4-15
receiver error messages, 4-16
source, 4-12
the 4 kHz signal, 8-11
trace with sampler correction off,
 8-12
YO coil drive with analog bus, 7-10
check front panel cables, 6-10
cleaning of connectors, 1-4
CLEAR LIST, 10-6
CMOS RAM, 10-7
coax cable, 1-3
codes for analog bus, 10-49
coefficients, 11-1
comb tooth at 3 GHz, 7-32
components related to specific error
 terms, 9-3
confidence check, 4-4
connection techniques, 1-4

connector
care of, 1-4

CONTINUE TEST, 10-5

controller HP-IB address, 4-5

controller troubleshooting, 4-7

conventions for symbols, 10-48

correction constants
ADC offset (test 52), 3-20
analog bus (test 46), 3-9
calibration kit default (test 57),
3-40
cavity oscillator frequency(test 54),
3-31
display intensity (test 49), 3-15
IF amplifier (test 51), 3-19
initialize EEPROMs (test 58), 3-41
option numbers (test 56), 3-39
retrieval from EEPROM backup
disk, 3-43
RF output power (test 47), 3-10
sampler magnitude (test 53), 3-21
serial number (test 55), 3-37
source default (test 44), 3-7
source pretune default (test 45),
3-8
source pretune (test 48), 3-14
Unprotected Hardware Option
Numbers, 3-62

CORRECTION CONSTANTS NOT
STORED, 10-51

CORRECTION TURNED OFF, 10-51

counter, 10-23

COUNTER
OFF, 10-24

counter (frequency), 1-2

counter readout location, 10-38

CPU
digital control, 12-10

CPU operation check, 6-4

CPU walking one pattern, 6-15

CRT demagnetizer or bulk tape eraser,
1-2

CURRENT PARAMETER NOT IN CAL
SET, 10-51

D

damage to center conductors, 9-3

data that is faulty, 4-17

DEADLOCK, 10-51

default correction constants
adjustment for source, 3-7

default correction constants
adjustment for source pretune,
3-8

default for calibration kit adjustment,
3-40

degaussing (demagnetizing) the
display, 3-46

DELETE, 10-6

demagnetizer or bulk tape eraser,
1-2

demagnetizing (degaussing)the
display, 3-46

description of tests, 10-7

DEVICE
not on, not connect, wrong addrs,
10-52

diagnose softkey, 10-7

diagnostic
error terms, 11-1

diagnostic LEDs for A15, 5-4

diagnostic routines for phase lock,
7-38

diagnostics
internal, 10-2

diagnostics of analyzer, 4-3

diagnostic tests, 6-11

diagram
A4 sampler/mixer to phase lock
cable, 7-6

digital control group, 6-4

diagram of HP 8753D, 4-19
diagram of power supply, 5-23
DIF Control, 10-9
DIF Counter, 10-9
digital control
 A10 digital IF, 12-10
 A16 rear panel, 12-12
 A18 display, 12-11
 A19 GSP, 12-11
 A1 front panel, 12-10
 A2 front panel processor, 12-10
 A9 CPU, 12-10
digital signal processor, 12-11
EEPROM, 12-11
main CPU, 12-10
main RAM, 12-11
 theory of operation, 12-8
digital control block diagram, 6-4
digital control check, 4-10
digital control lines observed using L INTCOP as trigger, 8-10
digital control signals A14-to-A13 check, 7-28
digital control signals check, 7-22
digital control signals generated from A14, 7-30
digital control troubleshooting chapter, 6-1
digital data lines observed using L INTCOP as trigger, 8-10
digital IF, 10-33, 12-29
 digital control, 12-10
digital voltmeter, 1-2
directivity (EDF and EDR), 11-10
disable shutdown circuitry, 5-16
disassembly procedures. *See* assembly replacement
DISK
 not on, not connected, wrong addrs, 10-52
disk drive check, 4-6
disk drive (external) HP-IB address, 4-5
disk (floppy), 1-2
DISK HARDWARE PROBLEM, 10-52
DISK MESSAGE LENGTH ERROR, 10-52
DISK READ/WRITE ERROR, 10-53
Disp 2 Ex., 10-13
Disp/cpu com., 10-15
display
 digital control, 12-11
 power, 12-8
display degaussing (demagnetizing), 3-46
displayed spurs with a filter, 3-33
display intensity correction constants adjustment, 3-15
display operation check, 6-7
display power supply on A19, 6-13
display tests, 10-3, 10-15
DISPLAY TESTS, 10-5
DIV FRAC N, 10-25
Divide-by-N Circuit Check, 7-28
DONE, 10-6
DRAM cell, 10-15
DSP ALU, 10-9
DSP Control, 10-9
DSP Intrpt, 10-9
DSP RAM, 10-9
DSP Wr/Rd, 10-9

E

earth ground wire and static-control table mat, 1-3
EDIT, 10-6
edit list menu, 10-6
equipment
 automated system verification, 2-6
cavity oscillator frequency adjustment, 3-31

display degaussing (demagnetizing), 3-46
display intensity correction constants adjustment, 3-15
EEPROM backup disk procedure, 3-42
external source mode frequency range, 2-26
fractional-N frequency range adjustment, 3-47
fractional-N spur avoidance and FM sideband adjustment, 3-56
frequency accuracy adjustment, 3-50
high/low band transition adjustment, 3-54
IF amplifier correction constants adjustment, 3-19
minimum R channel level, 2-34
RF output power correction constants adjustment, 3-10
sampler magnitude adjustment, 3-21
source spur avoidance tracking adjustment, 3-60
test port frequency range and accuracy test, 2-23
test port input noise floor level, 2-40
test port output power accuracy, 2-28
test port output power range and linearity, 2-31
vertical position and focus adjustment, 3-44
equipment for service, 1-1
error
 BATTERY FAILED. STATE MEMORY CLEARED, 10-50
 BATTERY LOW! STORE SAVE REGS TO DISK, 10-50

CALIBRATION ABORTED, 10-50
CALIBRATION REQUIRED, 10-51
CORRECTION CONSTANTS NOT STORED, 10-51
CORRECTION TURNED OFF, 10-51
CURRENT PARAMETER NOT IN CAL SET, 10-51
DEADLOCK, 10-51
DEVICE: not on, not connect, wrong addrs, 10-52
DISK HARDWARE PROBLEM, 10-52
DISK MESSAGE LENGTH ERROR, 10-52
DISK: not on, not connected, wrong addrs, 10-52
DISK READ/WRITE ERROR, 10-53
INITIALIZATION FAILED, 10-53
INSUFFICIENT MEMORY, PWR MTR CAL OFF, 10-53
NO CALIBRATION CURRENTLY IN PROGRESS, 10-53
NO IF FOUND: CHECK R INPUT LEVEL, 10-54
NO PHASE LOCK: CHECK R INPUT LEVEL, 10-54
NO SPACE FOR NEW CAL. CLEAR REGISTERS, 10-54
NOT ALLOWED DURING POWER METER CAL, 10-55
NOT ENOUGH SPACE ON DISK FOR STORE, 10-53
OVERLOAD ON INPUT A, POWER REDUCED, 10-55
OVERLOAD ON INPUT B, POWER REDUCED, 10-55
OVERLOAD ON INPUT R, POWER REDUCED, 10-55
PARALLEL PORT NOT AVAILABLE FOR COPY, 10-56

PARALLEL PORT NOT AVAILABLE
FOR GPIO, 10-55
PHASE LOCK CAL FAILED, 10-56
PHASE LOCK LOST, 10-56
POSSIBLE FALSE LOCK, 10-57
POWER SUPPLY HOT!, 10-58
POWER SUPPLY SHUT DOWN!,
10-58
POWER UNLEVELED, 10-57
POW MET INVALID, 10-57
POW MET: not on, not connected,
wrong addrs, 10-58
POW MET NOT SETTLED, 10-57
PRINTER: error, 10-58
PRINTER: not handshaking, 10-58
PRINTER: not on, not connected,
wrong addrs, 10-59
PROBE POWER SHUT DOWN!,
10-59
SAVE FAILED. INSUFFICIENT
MEMORY, 10-59
SELF TEST #n FAILED, 10-59
SOURCE POWER TRIPPED, RESET
UNDER POWER MENU, 10-60
SWEEP MODE CHANGED TO CW
TIME SWEEP, 10-60
SYSTEM IS NOT IN REMOTE, 10-60
TEST ABORTED, 10-60
TROUBLE! CHECK SETUP AND
START OVER, 10-61
WRONG DISK FORMAT, INITIALIZE
DISK, 10-61
error-correction procedure, 11-3
error message for phase lock, 7-4
error messages, 10-1, 10-50
error messages for receiver failure,
8-3
error term inspection, 9-3
error terms, 11-1
directivity (EDF and EDR), 11-10

isolation (crosstalk, EXF and EXR),
11-13
load Match (ELF and ELR), 11-14
reflection Tracking (ERF and ERR),
11-12
source match (ESF and ESR), 11-11
transmission tracking (ETF and
ETR), 11-15
E-terms, 11-1
external source, 1-2
external source mode frequency
range, 2-26
external tests, 10-3, 10-11
EXTERNAL TESTS, 10-4

F

failure
A11 phase lock and A3 source
check, 7-7
A19 GSP and A18 display operation,
6-7
A1/A2 front panel, 6-7
key stuck, 6-8
of operator's check, 4-4
of self test, 4-3
phase lock error, 7-4
receiver, 8-3
RF power from source, 7-3

failures
HP-IB, 6-18
fan
air flow detector, 12-7
variable fan circuit, 12-7
fan speeds, 5-21
fan troubleshooting, 5-21
fan voltages, 5-21
faulty analyzer repair, 4-2
faulty cables, 9-1
faulty calibration devices or
connectors, 9-1
faulty data, 4-17

faulty group isolation, 4-8
filter (low pass), 1-2
firmware revision softkey, 10-47
floor level test, 2-40
floppy disk, 1-2
FM Coil – plot with 3 point sweep, 7-36
FM sideband and spur avoidance adjustment, 3-56
FN Count., 10-10
FN LO at A12 check, 7-18
FN LO waveform at A12J1, 7-18
focus adjustment and vertical position adjustment, 3-44
FRAC N, 10-25
frac-N analog source, 12-13
Frac N Cont., 10-9
frac-N digital source, 12-13
FRACN TUNE mode HI OUT signal, 7-33
FRACN TUNE ON OFF, 10-18
Fractional-N Check, 7-23
fractional-N (digital), 10-43
fractional-N frequency range adjustment, 3-47
Fractional-N Frequency Range Adjustment Sequence, 3-64
fractional-N spur avoidance and FM sideband adjustment, 3-56
Fractional-N Spur Avoidance and FM Sideband Adjustment Sequence, 3-64
frequency accuracy adjustment, 3-50
frequency counter, 1-2, 10-23
frequency output in SRC tune mode, 7-7
frequency range and accuracy test, 2-23
frequency range for external source mode, 2-26
frequency range of fractional-N adjustment, 3-47
front panel assembly replacement, 14-8
digital control, 12-10
part numbers, 13-20-22
front panel key codes, 6-8
front panel probe power voltages, 5-19
front panel processor digital control, 12-10
front panel troubleshooting, 6-7
Fr Pan Diag., 10-11
Fr Pan Wr/Rd, 10-9
full two-port error-correction procedure, 11-3
functional group fault location, 4-8
functional groups theory of operation, 12-4
fuse check, 5-7

G

good trace display, 8-5
green LED on A15 power supply shutdown, 12-6
green LEDs on A8, 12-7
GSP digital control, 12-11
GSP operation check, 6-7

H

hardkeys, 10-2
hardware bottom view, 13-30
disk drive, 13-36
fan, 13-38
front view, 13-32
memory deck, 13-37
part numbers, 13-28-39

preregulator, 13-39
test set deck, 13-34
top view, 13-28
HB FLTR SW ON OFF, 10-19
Hewlett-Packard servicing, 4-2
high band REF signal, 7-16
high/low band transition adjustment, 3-54
High/Low Band Transition Adjustment Sequence, 3-64
high quality comb tooth at 3 GHz, 7-32
high stability frequency reference assembly replacement, 14-56
part numbers, 13-26
HI OUT signal in FRACN TUNE mode, 7-33
H MB line, 7-30
how to
adjust ADC offset correction constants, 3-20
adjust analog bus correction constants, 3-9
adjust calibration kit default correction constants, 3-40
adjust cavity oscillator frequency correction constants, 3-31
adjust display intensity correction constants, 3-15
adjust fractional-N frequency range, 3-47
adjust fractional-N spur avoidance and FM sideband, 3-56
adjust frequency accuracy, 3-50
adjust high/low band transition, 3-54
adjust IF amplifier correction constants, 3-19
adjustment the analyzer, 3-1
adjust option numbers correction constants, 3-39
adjust RF output power correction constants, 3-10
adjust sampler magnitude correction constants, 3-21
adjust serial number correction constants, 3-37
adjust source default correction constants, 3-7
adjust source pretune correction constants, 3-14
adjust source pretune default correction constants, 3-8
adjust source spur avoidance tracking, 3-60
adjust the analyzer using sequences, 3-64
adjust vertical position and focus, 3-44
backup the EEPROM disk, 3-42
clean connectors, 1-4
degauss (demagnetize) the display, 3-46
demagnetize (degauss) the display, 3-46
identify the faulty functional group, 4-8
initialize EEPROMs, 3-41
load sequences from disk, 3-64
performance test the analyzer, 2-2
position the A9 CC Jumper, 3-6
repair the analyzer, 4-1
retrieve correction constant data from EEPROM backup disk, 3-43
run the operator's check, 4-4
set up the fractional-N frequency range adjustment, 3-65
set up the fractional-N spur avoidance and FM sideband adjustment, 3-66

- set up the high/low band transition
 adjustments, 3-65
 test external source mode frequency
 range, 2-26
 test frequency range and accuracy,
 2-23
 test minimum R channel level,
 2-34
 test port input noise floor level,
 2-40
 test port output frequency range
 and accuracy, 2-23
 test port output power accuracy,
 2-28
 test port output power range and
 linearity, 2-31
 troubleshoot, 4-1
 troubleshoot accessories, 9-1
 troubleshoot broadband power
 problems, 7-38
 troubleshoot digital control group,
 6-1
 troubleshoot receiver, 8-1
 troubleshoot source group, 7-1
 verify analyzer operation, 2-2
 verify an analyzer system
 automatically, 2-6
 verify an analyzer system manually,
 2-14
 HP 8753D adjustments, 3-1
 HP 8753D block diagram, 4-19
 HP-IB addresses, 4-5
 HP-IB cable, 1-3
 HP-IB Failures, 6-18
 HP-IB mnemonic for service, 10-1
 HP-IB service mnemonic definitions,
 10-48
 HP-IB system check, 4-5
- I**
 IF amplifier correction constants
 adjustment, 3-19
 IF GAIN AUTO, 10-21
 IF GAIN OFF, 10-21
 IF GAIN ON, 10-21
 IF Step Cor., 10-13
 improper calibration technique, 9-1
 Init EEPROM, 10-14
 INITIALIZATION FAILED, 10-53
 initialize EEPROMs, 3-41
 initial observations, 4-3
 input noise floor level test, 2-40
 inputs (A and B) check, 8-4
 input traces check, 4-15
 inspect cables, 6-10
 inspect error terms, 9-3
 inspection of test port connectors
 and calibration devices, 9-3
 inspect the accessories, 9-3
INSUFFICIENT MEMORY, PWR MTR
 CAL OFF, 10-53
Inten DAC., 10-15
 intensity adjustment for display,
 3-15
Intensity Cor., 10-13
 internal diagnostics, 10-2
 internal diagnostic tests, 6-11
 internal tests, 10-3, 10-7
INTERNAL TESTS, 10-4
 invoking tests remotely, 10-48
 isolation (crosstalk, EXF and EXR),
 11-13
- J**
 jumper position, 10-8
 jumper position adjustment, 3-6
- K**
 key codes, 6-8
 key failure identification, 6-8

keys in service menu, 10-1
kit re-certification, 2-5
kits
 calibration kit 7 mm, 50Ω, 1-2
 calibration kit Type-N, 75Ω, 1-2
 tool, 1-2
 verification kit 7 mm, 1-2

L

LED front panel, 12-25
L ENREF line, 7-22
L HB and L LB Lines, 7-23
light occluder, 1-2
LIMITS NORM/SPCL, 10-5
linearity and range of power test, 2-31
line fuse check, 5-7
line power module
 theory of operation, 12-6
line voltage check, 5-7
L INTCOP as trigger to observe control lines, 8-10
L INTCOP as trigger to observe data lines, 8-10
L LB and L HB Lines, 7-23
LO (2ND) waveforms, 7-20
load device verification, 9-4
load Match (ELF and ELR), 11-14
location
 diagnostic LEDs for A15, 5-4
 post regulator test points, 5-5
 power supply cable, 5-8
 sales and service office, 15-3
lock error, 7-4
LO OUT waveform at A14J2, 7-27
LOSS/SENSR LISTS, 10-5
low band REF signal, 7-17
low pass filter, 1-2

M

magnitude of sampler adjustment, 3-21
main ADC, 10-23
Main DRAM, 10-7
MAIN PWR DAC, 10-19
Main VRAM, 10-15
major assemblies
 bottom view, 13-8
 part numbers, 13-6-8
 rebuilt-exchange, 13-3
 replacement procedures. *See*
 assembly replacement
 top view, 13-6
measurement calibration coefficients, 11-1
measurement calibration procedure, 11-3
measuring receiver, 1-2
mechanical adjustment sequences, 3-64
memory
 INSUFFICIENT MEMORY, PWR
 MTR CAL OFF, 10-53
menu
 analog in, 10-24
 edit list, 10-6
 peek/poke, 10-46
 service keys, 10-18
 service modes, 10-21
 test options, 10-5
 tests, 10-3
menus for service, 10-1
message
 BATTERY FAILED. STATE MEMORY CLEARED, 10-50
 BATTERY LOW! STORE SAVE REGS TO DISK, 10-50
 CALIBRATION ABORTED, 10-50
 CALIBRATION REQUIRED, 10-51

CORRECTION CONSTANTS NOT STORED, 10-51
CORRECTION TURNED OFF, 10-51
CURRENT PARAMETER NOT IN CAL SET, 10-51
DEADLOCK, 10-51
DEVICE: not on, not connect, wrong addrs, 10-52
DISK HARDWARE PROBLEM, 10-52
DISK MESSAGE LENGTH ERROR, 10-52
DISK: not on, not connected, wrong addrs, 10-52
DISK READ/WRITE ERROR, 10-53 error, 10-50
INITIALIZATION FAILED, 10-53
NO CALIBRATION CURRENTLY IN PROGRESS, 10-53
NO IF FOUND: CHECK R INPUT LEVEL, 10-54
NO PHASE LOCK: CHECK R INPUT LEVEL, 10-54
NO SPACE FOR NEW CAL. CLEAR REGISTERS, 10-54
NOT ALLOWED DURING POWER METER CAL, 10-55
NOT ENOUGH SPACE ON DISK FOR STORE, 10-53
OVERLOAD ON INPUT A, POWER REDUCED, 10-55
OVERLOAD ON INPUT B, POWER REDUCED, 10-55
OVERLOAD ON INPUT R, POWER REDUCED, 10-55
PARALLEL PORT NOT AVAILABLE FOR COPY, 10-56
PARALLEL PORT NOT AVAILABLE FOR GPIO, 10-55
PHASE LOCK CAL FAILED, 10-56
PHASE LOCK LOST, 10-56

POSSIBLE FALSE LOCK, 10-57
POWER SUPPLY HOT!, 10-58
POWER SUPPLY SHUT DOWN!, 10-58
POWER UNLEVELLED, 10-57
POW MET INVALID, 10-57
POW MET: not on, not connected, wrong addrs, 10-58
POW MET NOT SETTLED, 10-57
PRINTER: error, 10-58
PRINTER: not handshaking, 10-58
PRINTER: not on, not connected, wrong addrs, 10-59
PROBE POWER SHUT DOWN!, 10-59
SAVE FAILED. INSUFFICIENT MEMORY, 10-59
SELF TEST #n FAILED, 10-59
SOURCE POWER TRIPPED, RESET UNDER POWER MENU, 10-60
SWEEP MODE CHANGED TO CW TIME SWEEP, 10-60
SYSTEM IS NOT IN REMOTE, 10-60
TEST ABORTED, 10-60
TROUBLE! CHECK SETUP AND START OVER, 10-61
WRONG DISK FORMAT, INITIALIZE DISK, 10-61
message for phase lock error, 7-4
messages
error, 10-1
meter (power), 1-2
microprocessor
theory of operation, 12-3
microwave connector care, 1-4
minimum loss pad, 1-2
minimum R channel level, 2-34
mnemonic definitions, 10-48
mnemonics for service keys, 10-1
monitor ABUS node 16 for power, 4-14

motherboard check, 5-13

N

NO CALIBRATION CURRENTLY IN PROGRESS, 10-53

nodes for analog bus, 10-26

NO FILE(S) FOUND ON DISK, 10-54

NO IF FOUND

CHECK R INPUT LEVEL, 7-4, 7-37,
10-54

noise floor level test, 2-40

NO PHASE LOCK

CHECK R INPUT LEVEL, 7-4, 7-37,
10-54

NORMAL and ALTER jumper position
adjustment, 3-6

NO SPACE FOR NEW CAL. CLEAR
REGISTERS, 10-54

NOT ALLOWED DURING POWER
METER CAL, 10-55

NOT ENOUGH SPACE ON DISK FOR
STORE, 10-53

NRM and ALT jumper position
adjustment, 3-6

number (option) adjustment, 3-39

number (serial) adjustment, 3-37

O

offices

sales and service, 15-3

offset (ADC) adjustment, 3-20

open and short device verification,
9-6

open loop compared to phase locked
output in SRC tune mode, 7-9

operating temperature check, 5-13

operation check of A19 GSP and A18
display, 6-7

operation check of A9 CPU, 6-4

operation verification, 2-1

post-repair, 3-2, 14-60

operator's check, 4-4

Option 1D5

assembly replacement, 14-56

part numbers, 13-26

Option Cor., 10-14

option numbers correction constants

adjustment, 3-39

options

002 harmonic mode, 1-6

006 6 GHz operation, 1-6

010 time domain, 1-6

011 receiver configuration, 1-6

075 75Ω impedance, 1-7

1CM rack mount flange kit without
handles, 1-7

1CP rack mount flange kit with
handles, 1-7

1D5 high stability frequency
reference, 1-6

descriptions of, 13-46

options available, 1-6

oscilloscope, 1-2

oscilloscope check of reference
frequencies, 7-14

output frequency in SRC tune mode,
7-7

overall block diagram, 4-19

OVERLOAD ON INPUT A, POWER
REDUCED, 10-55

OVERLOAD ON INPUT B, POWER
REDUCED, 10-55

OVERLOAD ON INPUT R, POWER
REDUCED, 10-55

P

P?, 10-57

panel key codes, 6-8

PARALLEL PORT NOT AVAILABLE
FOR COPY, 10-56

PARALLEL PORT NOT AVAILABLE
FOR GPIO, 10-55

parts. *See* replaceable parts
patterns test, 10-16
PEEK, 10-46
PEEK/POKE, 10-46
PEEK/POKE ADDRESS, 10-46
peek/poke menu, 10-46
performance test record types, 2-4
performance tests
 1. Test Port Output Frequency
 Range and Accuracy, 2-23
 2. External Source Mode Frequency
 Range, 2-26
 3. Test Port Output Power Accuracy,
 2-28
 4. Test Port Output Power Range
 and Linearity, 2-31
 5. Minimum R Channel Level, 2-34
 6. Test Port Input Noise Floor
 Level, 2-40
chapter, 2-1
description of, 2-1
post-repair, 3-2, 14-60
peripheral equipment
 theory of operation, 12-3
peripheral HP-IB addresses, 4-5
peripheral troubleshooting, 4-7
phase lock, 10-34
 source, 12-14
phase lock (A11) check, 7-34
phase lock and A3 source check, 7-7
PHASE LOCK CAL FAILED, 7-4,
 7-37, 10-56
phase locked output compared to
 open loop in SRC tune mode,
 7-9
phase lock error, 7-4
phase lock error messages, 7-37
phase lock error messages check,
 4-12
PHASE LOCK LOST, 7-4, 7-37, 10-56
photometer probe, 1-2
Pin Locations on A19J5, 6-13
pin locations on connector of W20,
 6-16
PLL AUTO ON OFF, 10-20
PLL DIAG ON OFF, 10-20
PLL PAUSE, 10-20
plotter HP-IB address, 4-5
plotter or printer check, 4-6
PLREF waveforms, 7-16
POKE, 10-46
Port 1 Op Chk., 10-11
Port 2 Op Chk., 10-11
port input noise floor level test, 2-40
port output power accuracy test,
 2-28
POSSIBLE FALSE LOCK, 10-57
Post Reg., 10-9
post regulator
 air flow detector, 12-7
 display power, 12-8
 green LEDs, 12-7
 probe power, 12-8
 shutdown circuit, 12-7
 theory of operation, 12-7
 variable fan circuit, 12-7
post regulator test point locations,
 5-5
post-repair procedures, 3-2, 14-60
power accuracy test, 2-28
power from source, 7-3
POWER LOSS, 10-5, 10-6
power meter (HP-IB), 1-2
power meter HP-IB address, 4-5
power output check, 4-12
power problems (broadband), 7-38
power range and linearity test, 2-31
power sensor, 1-2
power splitter, 1-2
power supply
 theory of operation, 12-5
power supply block diagram, 5-23

power supply cable location, 5-8
power supply check, 4-9
power supply functional group block diagram, 5-3
POWER SUPPLY HOT!, 10-58
power supply on A19, 6-13
power supply shutdown
 A15 green LED, 12-6
 A15 red LED, 12-6
 theory of operation, 12-6
POWER SUPPLY SHUT DOWN!, 10-58
power supply troubleshooting chapter, 5-1
POWER UNLEVELED, 10-57
power up sequence check, 4-10
POW MET
 not on, not connected, wrong addrs, 10-58
POW MET INVALID, 10-57
POW MET NOT SETTLED, 10-57
precision frequency reference
 assembly replacement, 14-56
 part numbers, 13-26
preregulated voltages
 theory of operation, 12-6
preregulator
 theory of operation, 12-5
preregulator LEDs check, 4-9
preregulator voltages, 5-10
PRESET, 10-7
preset sequence, 4-3, 6-8
Pretune Cor., 10-13
Pretune Def., 10-13
preventive maintenance, 11-1
principles of microwave connector
 care, 1-4
printer, 1-2
PRINTER
 error, 10-58
 not handshaking, 10-58
not on, not connected, wrong addrs, 10-59
printer HP-IB address, 4-5
probe
 power, 12-8
probe (photometer), 1-2
PROBE POWER SHUT DOWN!, 10-59
probe power voltages, 5-19
procedure
 spur search with a filter, 3-33
 spur search without a filter, 3-34
procedures
 A9 CC Jumper Positions, 3-6
 ADC Offset Correction Constants (Test 52), 3-20
 Analog Bus Correction Constant (Test 46), 3-9
 Calibration Kit Default Correction Constants (Test 57), 3-40
 Cavity Oscillator Frequency Correction Constants (Test 54), 3-31
 Display Degaussing (Demagnetizing), 3-46
 Display Intensity Correction Constants (Test 49), 3-15
 EEPROM Backup Disk, 3-42
 external source mode frequency range, 2-26
 Fractional-N Frequency Range Adjustment, 3-47
 Fractional-N Spur Avoidance and FM Sideband Adjustment, 3-56
 Frequency Accuracy Adjustment, 3-50
 High/Low Band Transition Adjustment, 3-54
 IF Amplifier Correction Constants (Test 51), 3-19
 Initialize EEPROMs (Test 58), 3-41
 minimum R channel level, 2-34

Option Numbers Correction
 Constant (Test 56), 3-39
retrieve correction constant data
 from EEPROM backup disk,
 3-43
RF Output Power Correction
 Constants (Test 47), 3-10
Sampler Magnitude and Phase
 Correction Constants (Test 53),
 3-21
Sequences for Mechanical
 Adjustments, 3-64
Serial Number Correction Constant
 (Test 55), 3-37
Source Default Correction Constants
 (Test 44), 3-7
Source Pretune Correction
 Constants (Test 48), 3-14
Source Pretune Default Correction
 Constants (Test 45), 3-8
Source Spur Avoidance Tracking
 Adjustment, 3-60
Test Port Input Noise Floor Level,
 2-40
test port output frequency range
 and accuracy, 2-23
test port output power accuracy,
 2-28
test port output power range and
 linearity, 2-31
Unprotected Hardware Option
 Numbers Correction Constants,
 3-62
verify an analyzer system
 (automated), 2-6
verify an analyzer system (manual
 mode), 2-14
Vertical Position and Focus
 Adjustments, 3-44
pulse generator
 source, 12-14

pulse generator (A7) check, 7-31
pulses (100 kHz), 7-15

R

range and accuracy of frequency,
 2-23
R channel level, 2-34
rear panel
 assembly replacement, 14-12
 digital control, 12-12
 part numbers, 13-24-26
Rear Panel, 10-9
rear panel LEDs check, 4-9
rebuilt-exchange assemblies, 13-3
receiver
 digital IF, 12-29
 sampler/mixer, 12-28
 theory of operation, 12-3, 12-27
receiver check, 4-15
receiver error messages, 4-16
receiver failure error messages, 8-3
receiver (measuring), 1-2
receiver troubleshooting chapter,
 8-1
RECORD ON OFF, 10-5
red LED on A15
 power supply shutdown, 12-6
REF (4 MHz) signal check, 8-7
reference
 source, 12-13
reference, A12, 10-40
reference (A12) check, 7-12
reference frequencies check using
 analog bus, 7-12
reference frequencies check using
 oscilloscope, 7-14
reference signal (4 MHz), 7-19
reflection Tracking (ERF and ERR),
 11-12
REF signal At A11TP1 Pin 9, 7-16
removing

A8, 5-14
line fuse, 5-7
repair procedure, 4-1
REPEAT ON OFF, 10-5
replaceable parts, 13-1
abbreviations, 13-46
battery, 13-8
cables, bottom, 13-12
cables, front, 13-14
cables, rear, 13-16
cables, source, 13-18
cables, top, 13-10
chassis, inside, 13-42
chassis, outside, 13-40
documentation, 13-44
ESD supplies, 13-45
front panel, inside, 13-22
front panel, outside, 13-20
fuse, preregulator, 13-39
fuses, post regulator, 13-45
fuses, rear panel, 13-24
handles, 13-45
hardware, bottom, 13-30
hardware, disk drive support, 13-36
hardware, fan, 13-38
hardware, front, 13-32
hardware, memory deck, 13-37
hardware, preregulator, 13-39
hardware, test set deck, 13-34
hardware, top, 13-28
major assemblies, bottom, 13-8
major assemblies, top, 13-6
miscellaneous, 13-44, 13-45
option descriptions, 13-46
ordering, 13-3
rear panel, 13-24
rear panel, Option 1D5, 13-26
rebuilt-exchange assemblies, 13-3
reference designations, 13-46
service tools, 13-44
touch-up paint, 13-45
upgrade kits, 13-44
replacement procedures. *See assembly replacement*
required tools, 1-1
RESET MEMORY, 10-46
return analyzer for repair, 4-2
revision (firmware) softkey, 10-47
RF cable set, 1-3
RF output power correction constants
 adjustment, 3-10
RF power from source, 7-3
RGB outputs, 10-15
ROM, 10-7

S

sales and service offices, 15-3
Sampler Cor., 10-13
SAMPLER COR ON OFF, 10-21
sampler correction off when checking
 the trace, 8-12
sampler magnitude correction
 constants adjustment, 3-21
sampler/mixer, 12-28
 2nd LO signal, 12-28
 high band, 12-28
 low band, 12-28
 mixer circuit, 12-29
 super low band, 12-28
SAVE FAILED. INSUFFICIENT
 MEMORY, 10-59
search for spurs with a filter, 3-33
search for spurs without a filter, 3-34
SEGMENT, 10-6
selector switch check, 5-7
self diagnose softkey, 10-7
self-test, 4-3
SELF TEST #n FAILED, 10-59
sensor (power), 1-2
sequence check for power up, 4-10
sequence contents, 3-66

sequence contents for Fractional-N Avoidance and FM Sideband Adjustment, 3-68

sequence contents for Fractional-N Frequency Range Adjustment, 3-67

sequence contents for High/Low Band Transition Adjustment, 3-66

sequence contents for VCO adjustment, 3-67

sequences

- Fractional-N Frequency Range Adjustment, 3-64
- Fractional-N Spur Avoidance and FM Sideband Adjustment, 3-64
- High/Low Band Transition Adjustment, 3-64

Serial Cor., 10-14

serial number correction constants adjustment, 3-37

service and support options, 1-8

service center procedure, 4-2

service features, 10-18

service key menus, 10-1

- service features, 10-18

service key mnemonics, 10-1

service mnemonic definitions, 10-48

SERVICE MODES, 10-18

service modes more menu, 10-21

service test equipment, 1-1

service tools list, 1-1

servicing the analyzer, 4-2

setup

- cavity oscillator frequency correction constant routine, 3-32
- external source mode frequency range, 2-27
- fractional-N spur avoidance and FM sideband adjustment, 3-57

frequency accuracy adjustment, 3-51

insertion loss measurement, 3-23

manual system verification, 2-14

maximum intensity adjustment, 3-17

minimum R channel level, 2-35

mismatch device verification, 2-12

mismatch device verification (manual mode), 2-20

phase lock error troubleshooting, 7-4

RF output correction constants, 3-12

sampler correction routine, 3-25

source power check, 4-13

test port frequency range and accuracy test, 2-24

test port input noise floor level, 2-41

test port output power accuracy, 2-29

test port output power range and linearity, 2-32

transmission calibration, 2-9, 2-17

vertical position and focus adjustment, 3-45

setup check for disk drive, 4-6

setup check for plotter or printer, 4-6

short and open device verification, 9-6

shutdown circuit

- post regulator, 12-7

shutdown circuit on A8, 12-7

shutdown circuitry disable, 5-16

signal examination for phase lock, 7-35

signal separation

- built-in test set, 12-25
- theory of operation, 12-25

signals required for A10 assembly operation, 8-8
SLOPE DAC, 10-19
softkeys, 10-2
source
 A11 phase lock, 12-14
 A12 reference, 12-13
 A13 frac-N analog, 12-13
 A14 frac-N digital, 12-13
 A3 source, 12-14
 A7 pulse generator, 12-14
 external source mode, 12-22
 frequency offset, 12-21
 harmonic analysis, 12-21
 high band theory, 12-18
 low band theory, 12-15
 operation in other modes, 12-21
 source, 12-14
 super low band theory, 12-14
 theory of operation, 12-2, 12-13
 tuned receiver mode, 12-24
source and A11 phase lock check, 7-7
source attenuator
 theory of operation, 12-2
source check, 4-12
Source Cor., 10-13
Source Def., 10-13
source default correction constants
 adjustment, 3-7
Source Ex., 10-11
source (external), 1-2
source group assemblies, 7-1
source group troubleshooting
 appendix, 7-37
source match (ESF and ESR), 11-11
source mode frequency range, 2-26
SOURCE PLL ON OFF, 10-19
source power, 7-3
SOURCE POWER TRIPPED, RESET
 UNDER POWER MENU, 10-60
source pretune correction constants
 adjustment, 3-14
source pretune default correction
 constants adjustment, 3-8
source spur avoidance tracking
 adjustment, 3-60
source troubleshooting chapter, 7-1
specifications
 external source mode frequency
 range, 2-26
 minimum R channel level, 2-34
 test port input noise floor level,
 2-40
 test port output frequency range
 and accuracy, 2-23
 test port output power accuracy,
 2-28
 test port output power range and
 linearity, 2-31
spectrum analyzer, 1-2
speed
 fan, 5-21
spikes display (acceptable versus
 excessive), 3-61
splitter (power), 1-2
spur avoidance and FM sideband
 adjustment, 3-56
spur avoidance tracking adjustment,
 3-60
SPUR AVOID ON OFF, 10-22
spurs displayed with a filter, 3-33
spur search with a filter, 3-33
spur search without a filter, 3-34
SPUR TEST ON OFF, 10-21
SRC ADJUST DACS, 10-19
SRC ADJUST MENU, 10-19
SRC TUNE FREQ, 10-19
SRC tune mode frequency output,
 7-7
SRC tune mode phase locked output
 compared to open loop, 7-9

- SRC tune mode waveform integrity, 7-8
- SRC TUNE ON OFF, 10-19
- stable HI OUT signal in FRACN TUNE mode, 7-33
- Start Troubleshooting chapter, 4-1
- static-control table mat and earth ground wire, 1-3
- status terms for test, 10-4
- step attenuator, 1-2
- STORE EEPROM ON OFF, 10-21
- stuck key identification, 6-8
- support and service options, 1-8
- SWEEP MODE CHANGED TO CW TIME SWEEP**, 10-60
- Sweep Trig., 10-10
- symbol conventions, 10-48
- SYSTEM IS NOT IN REMOTE**, 10-60
- system performance uncorrected, 11-8
- system verification
- description of, 2-1
 - post-repair, 3-2, 14-60
- system verification (automated), 2-6
- system verification cycle, 2-5
- system verification (manual), 2-14
- system verification tests, 10-3, 10-12
- Sys Ver Init., 10-12
- SYS VER TESTS**, 10-4
- T**
- table of service tools, 1-1
- temperature check, 5-13
- terms for test status, 10-4
- test 44, 3-7, 10-13
- test 45, 3-8, 10-13
- test 46, 3-9, 10-13
- test 47, 3-10, 10-13
- test 48, 3-14, 10-13
- test 49, 3-15, 10-13
- test 50, 10-13
- test 51, 3-19, 10-13
- test 52, 3-20, 10-13
- test 53, 3-21, 10-13
- test 54, 3-31, 10-13
- test 55, 3-37, 10-14
- test 56, 3-39, 10-14
- test 57, 3-40, 10-14
- test 58, 3-41, 10-14
- test 59, 10-15
- test 60, 10-15
- test 61, 10-15
- test 62, 10-15
- test 63, 10-15
- test 64, 10-15
- test 65, 10-15
- test 66, 10-16
- test 67-69, 10-16
- test 70, 10-16
- test 71, 10-16
- test 72, 10-16
- test 73-74, 10-16
- test 75, 10-17
- test 76, 10-17
- test 77, 10-17
- test 78, 10-17
- test 79, 10-17
- test 80, 10-17
- TEST ABORTED**, 10-60
- test cables, 9-5
- test descriptions, 10-7
- test equipment for service, 1-1
- TEST OPTIONS**, 10-5
- test options menu, 10-5
- Test Pat 1., 10-16
- Test Pat 10., 10-17
- Test Pat 11., 10-17
- Test Pat 12., 10-17
- Test Pat 13., 10-17
- Test Pat 14., 10-17
- Test Pat 15., 10-17
- Test Pat 2-4., 10-16

Test Pat 5., 10-16
Test Pat 6., 10-16
Test Pat 7., 10-16
Test Pat 8-9, 10-16
test patterns, 10-3
test port connector inspection, 9-3
test port couplers, 12-25
test port input noise floor level, 2-40
test port output frequency range and
 accuracy test, 2-23
test port output power accuracy,
 2-28
test port output power range and
 linearity, 2-31
test record types, 2-4
tests
 1. Test Port Output Frequency
 Range and Accuracy, 2-23
 2. External Source Mode Frequency
 Range, 2-26
adjustments, 10-13
chapter, 2-1
display, 10-15
external, 10-11
internal, 10-7
minimum R channel level, 2-34
patterns, 10-16
system verification, 10-12
Test Port Input Noise Floor Level:
 2-40
Test Port Output Power Accuracy,
 2-28
Test Port Output Power Range and
 Linearity, 2-31
tests (diagnostics), 6-11
test set, 12-25
 LED front panel, 12-25
 test port couplers, 12-25
 test set interface, 12-25
 theory of operation, 12-3
 transfer switch, 12-25
test set interface, 12-25
tests menu, 10-3
test status terms, 10-4
theory of operation, 12-1
 +5 V digital supply, 12-6
A15 green LED, 12-6
A15 preregulator, 12-5
A15 red LED, 12-6
A3 source, 12-2, 12-13
A8 green LEDs, 12-7
A8 post regulator, 12-7
A8 shutdown circuit, 12-7
air flow detector, 12-7
digital control, 12-8
display power, 12-8
functional groups, 12-4
line power module, 12-6
microprocessor, 12-3
peripheral equipment, 12-3
power supply, 12-5
power supply shutdown, 12-6
preregulated voltages, 12-6
probe power, 12-8
receiver, 12-3, 12-27
signal separation, 12-25
source attenuator, 12-2
test set, 12-3
 variable fan circuit, 12-7
tool kit, 1-2
tools for service, 1-1
trace (good) display, 8-5
trace with sampler correction on and
 off, 8-13
tracking for source spur avoidance
 adjustment, 3-60
transfer switch, 12-25
transmission tracking (ETF and ETR),
 11-15
TROUBLE! CHECK SETUP AND
 START OVER, 10-61
troubleshooting

- 1st LO signal at sampler/mixer, 8-14
 A10 by substitution or signal examination, 8-8
 A11 phase lock, 7-34
 A11 phase lock and A3 source check, 7-7
 A12 reference, 7-12
 A13/A14 Fractional-N, 7-23
 A14 Divide-by-N Circuit Check, 7-28
 A15 preregulator, 5-9
 A1/A2 front panel, 6-7
 A7 pulse generator, 7-31
 accessories, 4-18, 9-1
 broadband power problems, 7-38
 diagnostics, 4-3
 digital control, 6-1
 disk drive, 4-6
 fan, 5-21
 faulty data, 4-17
 faulty group identification, 4-8
 first step, 4-1
 front panel, 6-7
 HP-IB systems, 4-5
 one or more inputs look good, 8-11
 phase lock error, 7-4
 plotters or printers, 4-6
 receiver, 8-1
 receiver error messages, 4-16
 self-test, 4-3
 source, 7-1
 start, 4-1
 systems with controllers, 4-7
 systems with multiple peripherals, 4-7
 when all inputs look bad, 8-6
 YO coil drive check with analog bus, 7-10
 troubleshooting power supply, 5-1
- troubleshooting source group appendix, 7-37
 two-port error-correction procedure, 11-3
- U**
- uncorrected performance, 11-8
 unprotected hardware option numbers correction constants, 3-62
 USE SENSOR A/B, 10-6
- V**
- variable fan circuit, 12-7
 VCO (A14) exercise, 7-26
 VCO range check frequencies, 7-23
 /Ver Dev 1., 10-12
 Ver Dev 2., 10-12
 Ver Dev 3., 10-12
 Ver Dev 4., 10-12
 verification cycle, kit re-certification, 2-5
 verification kit 7 mm, 1-2
 verification procedures post-repair, 3-2, 14-60
 verify calibration kit devices, 9-4
 vertical position and focus adjustment, 3-44
 voltage indications post regulator, 12-7
 voltages
 A15 preregulator check, 5-10
 A19 GSP, 6-14
 A8, 5-14
 display power supply, 6-13
 fan, 5-21
 front panel probe power, 5-19
 YO- and YO+ coil drive voltage differences with& SOURCE PLL OFF, 7-12
 voltages for post regulator, 5-5
 voltmeter, 1-2

VRAM bank., 10-15
VRAM/video, 10-15

W

walking one pattern, 6-15
warranty explanation, 4-2
waveform integrity in SRC tune mode,
7-8
wrist strap and cord (antistatic), 1-3

WRONG DISK FORMAT, INITIALIZE
DISK, 10-61

Y

YO coil drive check with analog bus,
7-10
YO- and YO+ coil drive voltage
differences with& SOURCE PLL
OFF, 7-12